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**ETSI** 

# Foreword

This Technical Specification has been produced by the 3rd Generation Partnership Project (3GPP).

The contents of the present document are subject to continuing work within the TSG and may change following formal TSG approval. Should the TSG modify the contents of the present document, it will be re-released by the TSG with an identifying change of release date and an increase in version number as follows:

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- z the third digit is incremented when editorial only changes have been incorporated in the document.

The present document is part 2 of a multi-part Technical Specification (TS) covering the New Radio (NR) User Equipment (UE) conformance specification, which is divided in the following parts:

3GPP TS 38.521-1 [13]: NR; User Equipment (UE) conformance specification; Radio transmission and reception; Part 1: Range 1 Standalone;

# 3GPP TS 38.521-2: NR; User Equipment (UE) conformance specification; Radio transmission and reception; Part 2: Range 2 Standalone;

3GPP TS 38.521-3 [14]: NR; User Equipment (UE) conformance specification; Radio transmission and reception; Part 3: Range 1 and Range 2 Interworking operation with other radios;

3GPP TS 38.521-4 [15]: NR; User Equipment conformance specification; Radio transmission and reception; Part 4: Performance;

3GPP TS 38.522 [16]: NR; User Equipment (UE) conformance specification; Applicability of radio transmission, radio reception and radio resource management test cases;

3GPP TS 38.533 [17]: NR; User Equipment (UE) conformance specification; Radio resource management (RRM);

# 1 Scope

The present document specifies the measurement procedures for the conformance test of the user equipment (UE) that contain RF characteristics for frequency Range 2 as part of the 5G-NR.

The requirements are listed in different clauses only if the corresponding parameters deviate. More generally, tests are only applicable to those mobiles that are intended to support the appropriate functionality. To indicate the circumstances in which tests apply, this is noted in the "*definition and applicability*" part of the test.

For example only Release 15 and later UE declared to support 5G-NR shall be tested for this functionality. In the event that for some tests different conditions apply for different releases, this is indicated within the text of the test itself.

# 2 References

The following documents contain provisions which, through reference in this text, constitute provisions of the present document.

- References are either specific (identified by date of publication, edition number, version number, etc.) or non-specific.
- For a specific reference, subsequent revisions do not apply.
- For a non-specific reference, the latest version applies. In the case of a reference to a 3GPP document (including a GSM document), a non-specific reference implicitly refers to the latest version of that document *in the same Release as the present document*.
- [1] 3GPP.TR 21.905: "Vocabulary for 3GPP Specifications".
- [2] 3GPP TS 38.101-1: "NR; User Equipment (UE) radio transmission and reception; Part 1: Range 1 Standalone".
- [3] 3GPP TS 38.101-2: "NR; User Equipment (UE) radio transmission and reception; Part 2: Range 2 Standalone".
- [4] 3GPP TS 38.101-3: "NR; User Equipment (UE) radio transmission and reception; Part 3: Range 1 and Range 2 Interworking operation with other radios".
- [5] 3GPP TR 38.810: "Study on test methods for New Radio".
- [6] ITU-R Recommendation M.1545: "Measurement uncertainty as it applies to test limits for the terrestrial component of International Mobile Telecommunications-2000".
- [7] ITU-R Recommendation SM.329-10: "Unwanted emissions in the spurious domain".
- [8] FCC 47 CFR Part 30: "UPPER MICROWAVE FLEXIBLE USE SERVICE, §30.202 Power limits".
- [9] 3GPP TS 38.211: "NR; Physical channels and modulation".
- [10] 3GPP TS <u>38.508-1</u>: "5GS; User Equipment (UE) conformance specification; Part 1: Common test environment".
- [11] 3GPP TS <u>38.508-</u>2: "5GS; User Equipment (UE) conformance specification; Part 2: Common Implementation Conformance Statement (ICS) proforma".
- [12] 3GPP TS <u>38.50</u>9: "5GS; Special conformance testing functions for User Equipment (UE)".
- [13] 3GPP TS 38.521-1: "NR; User Equipment (UE) conformance specification; Radio transmission and reception; Part 1: Range 1 Standalone".
- [14] 3GPP TS 38.521-3: "NR; User Equipment (UE) conformance specification; Radio transmission and reception; Part 3: Range 1 and Range 2 Interworking operation with other radios".

- [15] 3GPP TS 38.521-4: "NR; User Equipment conformance specification; Radio transmission and reception; Part 4: Performance".
- [16] 3GPP TS <u>38.5</u>22: "NR; User Equipment (UE) conformance specification; Applicability of radio transmission, radio reception and radio resource management test cases".
- [17] 3GPP TS 38.533: "NR; User Equipment (UE) conformance specification; Radio resource management (RRM)".
- [18] 3GPP TS 38.300: "NR; Overall description; Stage 2".
- [19] 3GPP TS 38.331: "NR; Radio Resource Control (RRC); Protocol specification".
- [20] 3GPP TR 38.903: "NR; Derivation of test tolerances and measurement uncertainty for User Equipment (UE) conformance tests ".
- [21] 3GPP TR 38.905: "NR; Derivation of test points for radio transmission and reception conformance test cases".
- [22] 3GPP TS 38.213: "NR; Physical layer procedures for control".
- [23] 3GPP TS 38.214: "NR; Physical layer procedures for data".
- [24] 3GPP TS 38.215: "NR; Physical layer measurements".
- [25] 3GPP TS 38.133: "NR; Requirements for support of radio resource management".
- [26] 3GPP TS 38.306: "NR; User Equipment (UE) radio access capabilities".
- [27] IEEE Std 149: "IEEE Standard Test Procedures for Antennas", IEEE.
- [28] 3GPP TS 38.321: "NR; Medium Access Control (MAC) protocol specification".

# 3 Definitions, symbols and abbreviations

## 3.1 Definitions

For the purposes of the present document, the terms and definitions given in TR 21.905 [1] and the following apply. A term defined in the present document takes precedence over the definition of the same term, if any, in TR 21.905 [1].

Aggregated Channel Bandwidth: The RF bandwidth in which a UE transmits and receives multiple contiguously aggregated carriers.

**Beam correspondence:** the ability of the UE to select a suitable beam for UL transmission based on DL measurements with or without relying on UL beam sweeping.

**Carrier aggregation:** Aggregation of two or more component carriers in order to support wider transmission bandwidths.

**Carrier aggregation band:** A set of one or more operating bands across which multiple carriers are aggregated with a specific set of technical requirements.

**Carrier aggregation bandwidth class:** A class defined by the aggregated transmission bandwidth configuration and maximum number of component carriers supported by a UE.

**Carrier aggregation configuration**: A combination of CA operating band(s) and CA bandwidth class(es) supported by a UE.

NOTE: Carriers aggregated in each band can be contiguous or non-contiguous.

**EIRP**(Link=TX beam peak direction, Meas=Link angle): measurement of the EIRP of the UE such that the measurement angle is aligned with the beam peak direction within an acceptable measurement error uncertainty. EIRP (indicator to be measured) can be replaced by Frequency, EVM, carrier Leakage, In-band emission and OBW.

**EIRP**(Link=Link angle, Meas=Link angle): measurement of the UE such that the link angle is aligned with the measurement angle. EIRP (indicator to be measured) can be replaced by EIS, Frequency, EVM, carrier Leakage, Inband emission and OBW.

**EIRP**(Link=Spherical coverage grid, Meas=Link angle): measurement of the EIRP spherical coverage of the UE such that the EIRP link and measurement angles are aligned with the directions along the spherical coverage grid within an acceptable measurement error uncertainty. Alternatively, the spherical coverage grid can be replaced by the beam peak search grid as the results from the beam peak search can be re-used for spherical coverage.

**EIS (equivalent isotropic sensitivity):** sensitivity for an isotropic directivity device equivalent to the sensitivity of the discussed device exposed to an incoming wave from a defined AoA

NOTE 1: The sensitivity is the minimum received power level at which specific requirement is met.

NOTE 2: Isotropic directivity is equal in all directions (i.e. 0 dBi).

**EIS**(Link=RX beam peak direction, Meas=Link angle): measurement of the EIS of the UE such that the measurement angle is aligned with the RX beam peak direction within an acceptable measurement error uncertainty.

**Fallback group:** Group of carrier aggregation bandwidth classes for which it is mandatory for a UE to be able to fallback to lower order CA bandwidth class configuration. It is not mandatory for a UE to be able to fallback to lower order CA bandwidth class configuration that belongs to a different fallback group.

Inter-band carrier aggregation: Carrier aggregation of component carriers in different operating bands.

NOTE: Carriers aggregated in each band can be contiguous or non-contiguous.

Intra-band contiguous carrier aggregation: Contiguous carriers aggregated in the same operating band.

Intra-band non-contiguous carrier aggregation: Non-contiguous carriers aggregated in the same operating band.

**Link angle:** a DL-signal AoA from the view point of the UE, as described in Annex N. If the beam lock function is used to lock the UE beam(s), the link angle can become any arbitrary AoA once the beam lock has been activated.

**Measurement angle:** the angle of measurement of the desired metric from the view point of the UE, as described in Annex N.

**radiated interface boundary**: operating band specific radiated requirements reference point where the radiated requirements apply.

**radiated requirements reference point**: for the RF measurement setup, the radiated requirements reference point is located at the centre of the quiet zone. From the UE perspective the reference point is the input of the UE antenna array.

**RX beam peak direction**: direction where the maximum total component of RSRP and thus best total component of EIS is found.

**Sub-block:** This is one contiguous allocated block of spectrum for transmission and reception by the same UE. There may be multiple instances of sub-blocks within an RF bandwidth.

**TRP(Link=TX beam peak direction, Meas=TRP grid):** measurement of the TRP of the UE such that the measurement angles are aligned with the directions of the TRP grid points within an acceptable measurement uncertainty while the link angle is aligned with the TX beam peak direction

NOTE: For requirements based on EIRP/EIS, the radiated interface boundary is associated to the far-field region.

TX beam peak direction: direction where the maximum total component of EIRP is found.

**UE transmission bandwidth configuration:** Set of resource blocks located within the UE channel bandwidth which may be used for transmitting or receiving by the UE.

Vehicular UE: A UE embedded in a vehicle.

# 3.2 Symbols

For the purposes of the present document, the following symbols apply:

$\Delta EIRP_{BC}$	The beam correspondence tolerance, where $\Delta EIRP_{BC} = EIRP_2 - EIRP_1$
$\Delta F_{Global}$	Granularity of the global frequency raster
	cruitanity of the groom frequency ruster
$\Delta F_{Raster}$	Band dependent channel raster granularity
$\Delta f_{OOB}$	$\Delta$ Frequency of Out Of Band emission
$\Delta MB_{P,n}$	Allowed relaxation to each, minimum peak EIRP and reference sensitivity due to support for
, ii	multi-band operation, per band in a combination of supported bands
$\Delta MB_{S,n}$	Allowed relaxation to each, EIRP spherical coverage and EIS spherical coverage due to support
<u></u> ,,,,	for multi-band operation, per band in a combination of supported bands
$\Delta_{\rm RB}$	The starting frequency offset between the allocated RB and the measured non-allocated RB
$\Delta R_{\rm IB}$	Allowed reference sensitivity relaxation due to support for inter-band CA operation
$\sum MB_P$	Total allowed relaxation to each, minimum peak EIRP and reference sensitivity due to support for
<u></u> 1	multi-band operation, for all bands in a combination of supported bands
$\sum MB_S$	Total allowed relaxation to each, EIRP spherical coverage and EIS spherical coverage due to
<u></u> ;;;;;;;;;;;;;;;;;;;;;;;;;;;;;;;;;	support for multi-band operation, for all bands in a combination of supported bands
<b>BW</b> <sub>Channel</sub>	Channel bandwidth
BW <sub>Channel_CA</sub>	Aggregated channel bandwidth, expressed in MHz.
BW <sub>GB</sub>	max( BW <sub>GB,Channel(k)</sub> )
BW <sub>GB,Channel(k)</sub>	Minimum guardband defined in clause 5.3A.2 of carrier k
BW <sub>interferer</sub>	Bandwidth of the interferer
Ceil(x)	Rounding upwards; $ceil(x)$ is the smallest integer such that $ceil(x) \ge x$
EIRP <sub>max</sub>	The applicable maximum EIRP as specified in clause $6.2.1$
EIRP <sub>1</sub>	The measured total EIRP based on the beam the UE chooses autonomously (corresponding beam)
	to transmit in the direction of the incoming DL signal, which is based on beam correspondence
	without relying on UL beam sweeping
EIRP <sub>2</sub>	The measured total EIRP based on the beam yielding highest EIRP in a given direction, which is
2	based on beam correspondence with relying on UL beam sweeping
F <sub>C</sub>	<i>RF reference frequency</i> for the carrier center on the channel raster, given in table 5.4.2.2-1
F <sub>C,block, high</sub>	Fc of the highest transmitted/received carrier in a sub-block.
F <sub>C,block, low</sub>	Fc of the lowest transmitted/received carrier in a sub-block.
F <sub>C, high</sub>	The Fc of the highest carrier, expressed in MHz.
F <sub>C, low</sub>	The Fc of the lowest carrier, expressed in MHz.
0,101	
$F_{DL_{high}}$	The highest frequency of the downlink operating band
F <sub>DL_low</sub>	The lowest frequency of the downlink operating band
Fedge, block, high	The upper sub-block edge, where $F_{edge,block,high} = F_{C,block,high} + F_{offset, high}$ .
Fedge, block, low	The lower sub-block edge, where $F_{edge,block,low} = F_{C,block,low} - F_{offset, low}$ .
Fedge, high	The upper edge of Aggregated Channel Bandwidth, expressed in MHz. $F_{edge, high} = F_{C, high} + F_{offset}$ ,
	high.
Fedge, low	The lower edge of <i>Aggregated Channel Bandwidth</i> , expressed in MHz. F <sub>edge, low</sub> = F <sub>C, low</sub> - F <sub>offset, low</sub> .
FInterferer	Frequency of the interferer
FInterferer (offset)	Frequency offset of the interferer (between the center frequency of the interferer and the carrier
	frequency of the carrier measured)
F <sub>Ioffset</sub>	Frequency offset of the interferer (between the center frequency of the interferer and the closest
	edge of the carrier measured)
Floor(x)	Rounding downwards; floor(x) is the greatest integer such that floor(x) $\leq$ x
FOOB	The boundary between the NR out of band emission and spurious emission domains
Foffset, high	Frequency offset from F <sub>C, high</sub> to the upper UE RF Bandwidth edge, or from F <sub>C,block, high</sub> to the upper
	sub-block edge
Foffset, low	Frequency offset from F <sub>C, low</sub> to the lower UE RF Bandwidth edge, or from F <sub>C,block, low</sub> to the lower
	sub-block edge
F <sub>REF</sub>	RF reference frequency
F <sub>REF-Offs</sub>	Offset used for calculating F <sub>REF</sub>
$F_{UL\_high}$	The highest frequency of the uplink operating band
$F_{UL\_low}$	The lowest frequency of the uplink operating band
$F_{UL\_Meas}$	The sub-carrier frequency for which the equalizer coefficient is evaluated
F_center	The center frequency of an allocated block of PRBs

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GB <sub>Channel</sub>	Minimum guardband defined in clause 5.3.3
L <sub>CRB</sub>	Transmission bandwidth which represents the length of a contiguous resource block allocation
	expressed in units of resources blocks
L <sub>CRB,Max</sub>	Maximum number of RB for a given Channel bandwidth and sub-carrier spacing
Max()	The largest of given numbers
Min()	The smallest of given numbers
MPR <sub>f,c</sub>	Maximum output power reduction for carrier f of serving cell c
<b>MPR</b> <sub>narrow</sub>	Maximum output power reduction due to narrow PRB allocation
MPR <sub>WT</sub>	Maximum power reduction due to modulation orders, transmit bandwidth configurations,
	waveform types
NR <sub>ACLR</sub>	NR ACLR
N <sub>RB</sub>	Transmission bandwidth configuration, expressed in units of resource blocks
N <sub>RB,high</sub>	Transmission bandwidth configurations according to Table 5.3.2-1 for the highest assigned
	component carrier in clause 5.3A.1
N <sub>RB,low</sub>	Transmission bandwidth configurations according to Table 5.3.2-1 for the lowest assigned
	component carrier in clause 5.3A.1
N <sub>REF</sub>	NR Absolute Radio Frequency Channel Number (NR-ARFCN)
N <sub>REF-Offs</sub>	Offset used for calculating N <sub>REF</sub>
$n_{\rm PRB}$	Physical resource block number
P <sub>CMAX</sub>	The configured maximum UE output power
$\mathbf{P}_{\mathrm{CMAX},f,c}$	The configured maximum UE output power for carrier f of serving cell c
PInterferer	Modulated mean power of the interferer
P <sub>int</sub>	The intermediate power point as defined in table 6.3.4.2-2
P <sub>max</sub>	The maximum UE output power as specified in clause 6.2.1
$\mathbf{P}_{\min}$	The minimum UE output power as specified in clause 6.3.1
P <sub>PowerClass</sub>	Nominal UE power class (i.e., no tolerance) as specified in clause 6.2.1
P <sub>RB</sub>	The transmitted power per allocated RB, measured in dBm
$P_{TMAX,f,c}$	The measured total radiated power for carrier $f$ of serving cell $c$
P <sub>UMAX</sub>	The measured configured maximum UE output power
Pw	Power of a wanted DL signal
P-MPR <sub>f,c</sub>	The Power Management UE Maximum Power Reduction for carrier f of serving cell c
RB <sub>start</sub>	Indicates the lowest RB index of transmitted resource blocks
SCS <sub>high</sub>	SCS for the highest assigned component carrier in clause 5.3A.1
$SCS_{low}$	SCS for the lowest assigned component carrier in clause 5.3A.1
SS <sub>REF</sub>	SS block reference frequency position
TRP <sub>max</sub>	The maximum TRP for the UE power class as specified in clause 6.2.1
$T(\Delta P)$	The tolerance $T(\Delta P)$ for applicable values of $\Delta P$ (values in dB)

# 3.3 Abbreviations

For the purposes of the present document, the abbreviations given in TR 21.905 [1] and the following apply. An abbreviation defined in the present document takes precedence over the definition of the same abbreviation, if any, in TR 21.905 [1].

ACLR	Adjacent Channel Leakage Ratio
ACS	Adjacent Channel Selectivity
AoA	Angle of Arrival
A-MPR	Additional Maximum Power Reduction
BCS	Bandwidth Combination Set
BPSK	Binary Phase-Shift Keying
BS	Base Station
BW	Bandwidth
BWP	Bandwidth Part
CA	Carrier Aggregation
CABW	Cumulative Aggregated Channel Bandwidth
CA_nX-nY	Inter-band CA of component carrier(s) in one sub-block within Band X and component carrier(s)
	in one sub-block within Band Y where X and Y are the applicable NR operating band
CC	Component Carrier
CDF	Cumulative Distribution Function
CP-OFDM	Cyclic Prefix-OFDM
CW	Continuous Wave
DFT-s-OFDM	Discrete Fourier Transform-spread-OFDM

DL	Downlink
DM-RS	Demodulation Reference Signal
DTX	Discontinuous Transmission
DUT	Device Under Test
EIRP	Effective Isotropic Radiated Power
EIS	Effective Isotropic Sensitivity
EVM	Error Vector Magnitude
FR	Frequency Range
FWA	Fixed Wireless Access
GSCN	Global Synchronization Channel Number
IBB	In-band Blocking
IDFT	Inverse Discrete Fourier Transformation
ITU-R	Radio communication Sector of the International Telecommunication Union
MBW	Measurement bandwidth defined for the protected band
MPR	Allowed maximum power reduction
NR	New Radio
NR-ARFCN	NR Absolute Radio Frequency Channel Number
OCNG	OFDMA Channel Noise Generator
OOB	Out-of-band
OTA	Over The Air
PRB	Physical Resource Block
P-MPR	Power Management Maximum Power Reduction
QAM	Quadrature Amplitude Modulation
RB	Resource Blocks
REFSENS	Reference Sensitivity
RF	Radio Frequency
RIB	Radiated Interface Boundary
RMS	Root Mean Square (value)
RSRP	Reference Signal Receiving Power
Rx	Receiver
SCS	Subcarrier Spacing
SEM	Spectrum Emission Mask
SRS	Sounding Reference Symbol
SS	Synchronization Symbol
TDD	Time Division Duplex
TPC	Transmission Power Control
TRP	Total Radiated Power
Tx	Transmitter
UE	User Equipment
UL	Uplink
UL MIMO	Uplink Multiple Antenna transmission

# 4 General

# 4.1 Relationship between minimum requirements and test requirements

The TS 38.101-2 [3] is a Single-RAT specification for NR UE, covering RF characteristics and minimum performance requirements. Conformance to the TS 38.101-2 [3] is demonstrated by fulfilling the test requirements specified in the present document.

The Minimum Requirements given in TS 38.101-2 [3] make no allowance for measurement uncertainty (MU). The measurement uncertainty defines in TR 38.903 [20]. The present document defines test tolerances (TT). These test tolerances are individually calculated for each test. The test tolerances are used to relax the minimum requirements in this specification to create test requirements. For some requirements, including regulatory requirements, the test tolerance is set to zero.

The measurement results returned by the test system are compared - without any modification - against the test requirements as defined by various levels of "Shared Risk" principle as described below.

a) Core specification value is not relaxed by any relaxation value (TT=0). For each single measurement, the probability of a borderline good UE being judged as FAIL equals the probability of a borderline bad UE being judged as PASS.

Test tolerances equal to 0 (TT=0) are considered in this specification.

- b) Core specification value is relaxed by a relaxation value (TT>0). For each single measurement, the probability of a borderline bad UE being judged as PASS is greater than the probability of a borderline good UE being judged as FAIL.
- Test tolerances lower than measurement uncertainty and greater than 0 (0 < TT < MU) are considered in this specification.
- Test tolerances high up to measurement uncertainty (TT = MU) are considered in this specification which is also known as "Never fail a good DUT" principle.
- c) Core specification value is tightened by a stringent value (TT<0). For each single measurement, the probability of a borderline good UE being judged as FAIL is greater than the probability of a borderline bad UE being judged as PASS.

Test tolerances lower than 0 (TT<0) are not considered in this specification.

The "Never fail a good DUT" and the "Shared Risk" principles are defined in Recommendation ITU R M.1545 [6].

## 4.2 Applicability of minimum requirements

- a) In TS 38.101-2 [3] the Minimum Requirements are specified as general requirements and additional requirements. Where the Requirement is specified as a general requirement, the requirement is mandated to be met in all scenarios.
- b) For specific scenarios for which an additional requirement is specified, in addition to meeting the general requirement, the UE is mandated to meet the additional requirements.
- c) The spurious emissions power requirements are for the long-term average of the power. For the purpose of reducing measurement uncertainty it is acceptable to average the measured power over a period of time sufficient to reduce the uncertainty due to the statistical nature of the signal.
- d) All the requirements for intra-band contiguous and non-contiguous CA apply under the assumption of the same slot format indicated by TDD-UL-DL-ConfigurationCommon and TDD-UL-DL-ConfigurationDedicated in the PCell and SCells for NR SA.

A terminal which supports CA or DC configurations, which include FR2 intra-band CA combinations with multiple subblocks, where at least one of the subblocks consists of a contiguous CA combination, is not required to support all possible fallback combinations but can directly fall back to a single FR2 carrier. Deactivating carriers within the CA or DC combination is still possible.

# 4.3 Specification suffix information

Unless stated otherwise the following suffixes are used for indicating at 2<sup>nd</sup> level clause, shown in Table 4.3-1.

Clause suffix	Variant
None	Single Carrier
А	Carrier Aggregation (CA)
В	Dual-Connectivity (DC)
С	Supplement Uplink (SUL)
D	UL MIMO
NOTE: Suffix D in this specification represents either polarized UL MIMO or spatial UL MIMO. RF requirements are same. If UE supports both kinds of UL MIMO, then RF requirements only need to be verified under either polarized or spatial UL MIMO.	

Table 4.3-1: Definition of suffixes

# 4.4 Test point analysis

The information on test point analysis and test point selection including number of test points for each test case is shown in TR 38.905 [21] clause 4.2.

# 4.5 Applicability and test coverage rules

The applicability and test coverage rules for Standalone and EN-DC capable devices shall include the following:

If a test case for a FR2 NR band in a device is tested in NSA mode for non-exceptional requirement as per TS 38.521-3 [14], it shall fulfil the coverage requirement for that test case for standalone FR2 test requirements for that NR band and need not be retested.

# 5 Operating bands and channel arrangement

# 5.1 General

The channel arrangements presented in this clause are based on the operating bands and channel bandwidths defined in the present release of specifications.

NOTE: Other operating bands and channel bandwidths may be considered in future releases.

Requirements throughout the RF specifications are in many cases defined separately for different frequency ranges (FR). The frequency ranges in which NR can operate according to this version of the specification are identified as described in Table 5.1-1.

Table 5.1-1: Definition of frequency ranges		
	Frequency range	Corresponding frequency range

designation	Corresponding nequency range
FR1	410 MHz – 7125 MHz
FR2	24250 MHz – 52600 MHz

The present specification covers FR2 operating bands.

# 5.2 Operating bands

NR is designed to operate in the FR2 operating bands defined in Table 5.2-1.

Operating Band	Uplink (UL) operating band BS receive UE transmit	Downlink (DL) operating band BS transmit UE receive	Duplex Mode
	$F_{UL_{low}} - F_{UL_{high}}$	$\mathbf{F}_{DL\_low} - \mathbf{F}_{DL\_high}$	
n257	26500 MHz – 29500 MHz	26500 MHz – 29500 MHz	TDD
n258	24250 MHz – 27500 MHz	24250 MHz – 27500 MHz	TDD
n260	37000 MHz – 40000 MHz	37000 MHz – 40000 MHz	TDD
n261	27500 MHz – 28350 MHz	27500 MHz – 28350 MHz	TDD

Table 5.2-1: NR operating bands in FR2

# 5.2A Operating bands for CA

### 5.2A.1 Intra-band CA

NR intra-band contiguous and non-contiguous carrier aggregation is designed to operate in the operating bands defined in Table 5.2A.1-1, where all operating bands are within FR2.

Table 5.2A.1-1: Intra-band	contiguous and nor	1-contiquous CA o	perating bands in FR2

NR CA Band	NR Band (Table 5.2-1)
CA_n257	n257
CA_n260	n260
CA_n261	n261

### 5.2A.2 Void

# 5.2D Operating bands for UL MIMO

NR UL MIMO is designed to operate in the operating bands defined in Table 5.2D-1.

#### Table 5.2D-1: NR UL MIMO operating bands

UL MIMO operating band (Table 5.2-1)		
n257		
n258		
n260		
n261		

# 5.3 UE Channel bandwidth

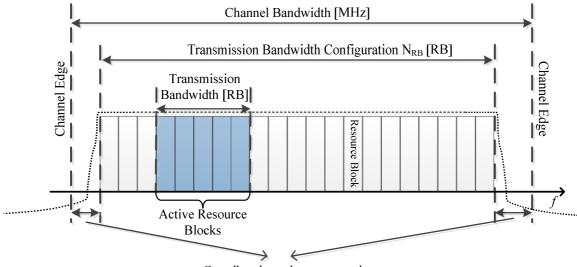
### 5.3.1 General

The UE channel bandwidth supports a single NR RF carrier in the uplink or downlink at the UE. From a BS perspective, different UE channel bandwidths may be supported within the same spectrum for transmitting to and receiving from UEs connected to the BS. Transmission of multiple carriers to the same UE (CA) or multiple carriers to different UEs within the BS channel bandwidth can be supported.

From a UE perspective, the UE is configured with one or more BWP / carriers, each with its own UE channel bandwidth. The UE does not need to be aware of the BS channel bandwidth or how the BS allocates bandwidth to different UEs.

The placement of the UE channel bandwidth for each UE carrier is flexible but can only be completely within the BS channel bandwidth.

The relationship between the channel bandwidth, the guardband and the transmission bandwidth configuration is shown in Figure 5.3.1-1.



Guardband, can be asymmetric

Figure 5.3.1-1: Definition of channel bandwidth and transmission bandwidth configuration for one NR channel

### 5.3.2 Maximum transmission bandwidth configuration

The maximum transmission bandwidth configuration  $N_{\text{RB}}$  for each UE channel bandwidth and subcarrier spacing is specified in Table 5.3.2-1

SCS (kHz)	50 MHz	100 MHz	200 MHz	400 MHz
	N <sub>RB</sub>	N <sub>RB</sub>	N <sub>RB</sub>	N <sub>RB</sub>
60	66	132	264	N/A
120	32	66	132	264

### 5.3.3 Minimum guardband and transmission bandwidth configuration

The minimum guardband for each UE channel bandwidth and SCS is specified in Table 5.3.3-1.

Table 5.3.3-1: Minimum guardband for each UE channel bandwidth and SCS (kHz)

SCS (kHz)	50 MHz	100 MHz	200 MHz	400 MHz
60	1210	2450	4930	N/A
120	1900	2420	4900	9860

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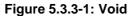
NOTE: The minimum guardbands have been calculated using the following equation:  $(BW_{Channel} \times 1000 (kHz) - N_{RB} \times SCS \times 12) / 2 - SCS/2$ , where  $N_{RB}$  are from Table 5.3.2-1.

The minimum guardband of receiving BS SCS 240 kHz SS/PBCH block for each UE channel bandwidth is specified in table 5.3.3-2 for FR2.

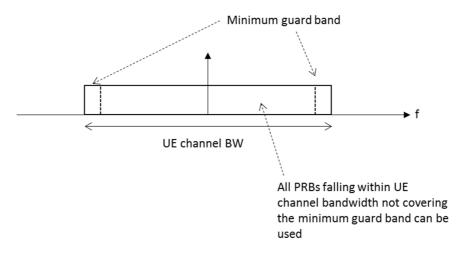
#### Table: 5.3.3-2: Minimum guardband (kHz) of SCS 240 kHz SS/PBCH block

SCS (kHz)	100 MHz	200 MHz	400 MHz
240	3800	7720	15560

NOTE: The minimum guardband in Table 5.3.3-2 is applicable only when the SCS 240 kHz SS/PBCH block is received adjacent to the edge of the UE channel bandwidth within which the SS/PBCH block is located.



The number of RBs configured in any channel bandwidth shall ensure that the minimum guardband specified in this clause is met.





In the case that multiple numerologies are multiplexed in the same symbol due to BS transmission of SSB, the minimum guardband on each side of the carrier is the guardband applied at the configured channel bandwidth for the numerology that is transmitted immediately adjacent to the guardband.

If multiple numerologies are multiplexed in the same symbol and the UE channel bandwidth is >200 MHz, the minimum guardband applied adjacent to 60 kHz SCS shall be the same as the minimum guardband defined for 120 kHz SCS for the same UE channel bandwidth.

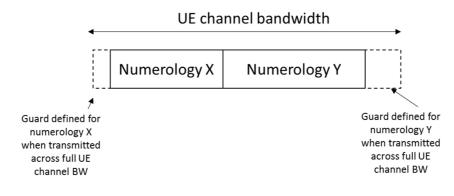


Figure 5.3.3-3: Guardband definition when transmitting multiple numerologies

NOTE: Figure 5.3.3-3 is not intended to imply the size of any guard between the two numerologies. Internumerology guardband within the carrier is implementation dependent.

### 5.3.4 RB alignment

For each numerology, its common resource blocks are specified in clause 4.4.4.3 in [9], and the starting point of its transmission bandwidth configuration on the common resource block grid for a given channel bandwidth is indicated by an offset to "Reference point A" in the unit of the numerology The *UE transmission bandwidth configuration* is indicated by the higher layer parameter *carrierBandwidth* [19] and will fulfil the minimum UE guardband requirement specified in clause 5.3.3.

### 5.3.5 Channel bandwidth per operating band

The requirements in this specification apply to the combination of channel bandwidths, SCS and operating bands shown in Table 5.3.5-1. The transmission bandwidth configuration in Table 5.3.2-1 shall be supported for each of the specified channel bandwidths. The channel bandwidths are specified for both the Tx and Rx path.

Operating	g band / S	SCS / UE	channe	bandwi	dth
Operating	SCS	50	100	200	400 <sup>2</sup>
band	kHz	MHz	MHz	MHz	MHz
n257	60	Yes	Yes	Yes	N/A
112.57	120	Yes	Yes	Yes	Yes
n258	60	Yes	Yes	Yes	N/A
11200	120	Yes	Yes	Yes	Yes
n260	60	Yes	Yes	Yes	N/A
1260	120	Yes	Yes	Yes	Yes
n261	60	Yes	Yes	Yes	N/A
11201	120	Yes	Yes	Yes	Yes
that use, by th	test confi smitter ar refer to tl if referer ne UE in S supporte	nd receive his table a nced SCS UL and/o	er tests ir and indica S value is r DL, sele	ate test S not supp ate the clo	CS to orted osest
NOTE 2: This		nel band	width is c		

## 5.3A UE Channel bandwidth for CA

### 5.3A.1 General

TBD

# 5.3A.2 Minimum guardband and transmission bandwidth configuration for CA

For intra-band contiguous carrier aggregation, *Aggregated Channel Bandwidth* and *Guard Bands* are defined as follows, see Figure 5.3A.2-1.

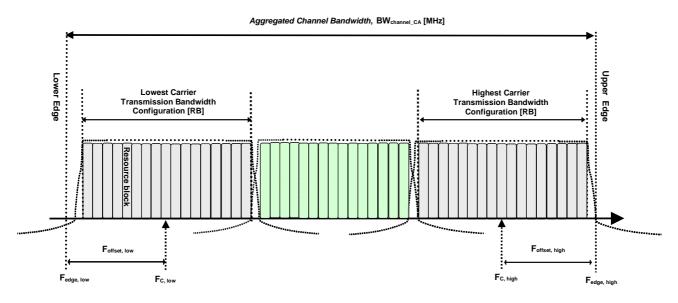


Figure 5.3A.2-1: Definition of Aggregated Channel Bandwidth for intra-band carrier aggregation

The aggregated channel bandwidth, BW<sub>Channel\_CA</sub>, is defined as

 $BW_{Channel_CA} = F_{edge,high} - F_{edge,low}$  (MHz).

The lower bandwidth edge  $F_{edge, low}$  and the upper bandwidth edge  $F_{edge, high}$  of the aggregated channel bandwidth are used as frequency reference points for transmitter and receiver requirements and are defined by

 $F_{edge,low} = F_{C,low} \text{ - } F_{offset,low}$ 

 $F_{edge,high} = F_{C,high} + F_{offset,high}$ 

The lower and upper frequency offsets depend on the transmission bandwidth configurations of the lowest and highest assigned edge component carrier and are defined as

$$\begin{split} F_{offset,low} &= (N_{RB,low}*12+1)*SCS_{low}/2 + BW_{GB} (MHz) \\ F_{offset,high} &= (N_{RB,high}*12 - 1)*SCS_{high}/2 + BW_{GB} (MHz) \\ BW_{GB} &= max(BW_{GB,Channel(k)}) \end{split}$$

 $N_{RB,low}$  and  $N_{RB,high}$  are the transmission bandwidth configurations according to Table 5.3.2-1 for the lowest and highest assigned component carrier,  $SCS_{low}$  and  $SCS_{high}$  are the sub-carrier spacing for the lowest and highest assigned component carrier respectively.  $SCS_{low}$ ,  $SCS_{high}$ ,  $N_{RB,low}$ ,  $N_{RB,high}$ , and  $BW_{GB,Channel(k)}$  use the largest  $\mu$  value among the subcarrier spacing configurations supported in the operating band for both of the channel bandwidths according to Table 5.3.5-1 and  $BW_{GB,Channel(k)}$  is the minimum guard band for carrier k according to Table 5.3.3-1 for the said  $\mu$  value.

For intra-band non-contiguous carrier aggregation *Sub-block Bandwidth* and *Sub-block edges* are defined as follows, see Figure 5.3A.2-2.

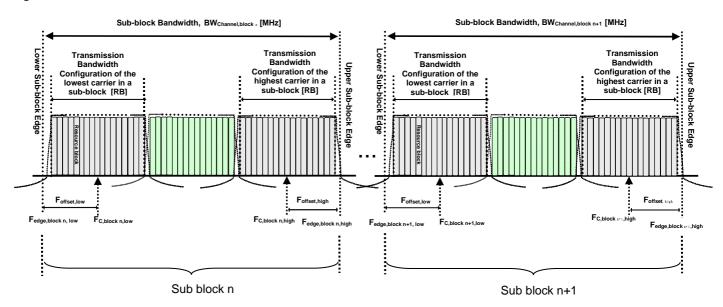


Figure 5.3A.2-2: Definition of sub-block bandwidth for intra-band non-contiguous spectrum

The lower sub-block edge of the Sub-block Bandwidth (BW<sub>Channel,block</sub>) is defined as

 $F_{edge,block, low} = F_{C,block,low} - F_{offset, low}$ 

The upper sub-block edge of the Sub-block Bandwidth is defined as

 $F_{edge,block,high} = F_{C,block,high} + F_{offset, high.}$ 

The Sub-block Bandwidth, BW<sub>Channel,block</sub>, is defined as follows:

 $BW_{Channel,block} = F_{edge,block,high} - F_{edge,block,low} (MHz)$ 

The lower and upper frequency offsets  $F_{offset,block,low}$  and  $F_{offset,block,high}$  depend on the transmission bandwidth configurations of the lowest and highest assigned edge component carriers within a sub-block and are defined as

$$\begin{split} F_{offset,block,low} &= (N_{RB,low}*12+1)*SCS_{low}/2 + BW_{GB} \mbox{ (MHz)} \\ F_{offset,block,high} &= (N_{RB,high}*12-1)*SCS_{high}/2 + BW_{GB} \mbox{ (MHz)} \\ BW_{GB} &= max(BW_{GB,Channel(k)}) \end{split}$$

where  $N_{RB,low}$  and  $N_{RB,high}$  are the transmission bandwidth configurations according to Table 5.3.2-1 for the lowest and highest assigned component carrier within a sub-block, respectively.  $SCS_{low}$ ,  $SCS_{high}$ ,  $N_{RB,low}$ ,  $N_{RB,high}$ , and  $BW_{GB,Channel(k)}$  use the largest  $\mu$  value among the subcarrier spacing configurations supported in the operating band for both of the channel bandwidths according to Table 5.3.5-1 and  $BW_{GB,Channel(k)}$  is the minimum guard band for carrier k according to Table 5.3.3-1 for the said  $\mu$  value. $SCS_{low}$  and  $SCS_{high}$  are the sub-carrier spacing for the lowest and highest assigned component carrier within a sub-block, respectively.

The sub-block gap size between two consecutive sub-blocks W<sub>gap</sub> is defined as

 $W_{gap} = F_{edge,block n+1,low -} F_{edge,block n,high} (MHz)$ 

### 5.3A.3 RB alignment with different numerologies for CA

TBD

# 5.3A.4 UE channel bandwidth per operating band for CA

For intra-band contiguous carrier aggregation, a carrier aggregation configuration is a single operating band supporting a carrier aggregation bandwidth class with associated bandwidth combination sets specified in clause 5.5A.1. For each carrier aggregation configuration, requirements are specified for all aggregated channel bandwidths contained in a bandwidth combination set, UE can indicate support of several bandwidth combination sets per carrier aggregation configuration. The requirements are applicable only when Uplink CCs are configured within the frequency range between lower edge of lowest downlink component carrier and upper edge of highest downlink component carrier.

For intra-band non-contiguous downlink carrier aggregation, a carrier aggregation configuration is a single operating band supporting two or more sub-blocks, each supporting a carrier aggregation bandwidth class. The requirements are applicable only when Uplink CCs are configured within the frequency range between lower edge of lowest downlink component carrier and upper edge of highest downlink component carrier.

Frequency separation class specified in Table 5.3A.4-2 indicates the maximum frequency span between lower edge of lowest component carrier and upper edge of highest component carrier that UE can support per band in downlink or uplink respectively in non-contiguous intra-band operation.

For inter-band carrier aggregation, a carrier aggregation configuration is a combination of operating bands, each supporting a carrier aggregation bandwidth class.

NR CA bandwidth class	Aggregated channel bandwidth	Number of contiguous CC	Fallback group
A	BW <sub>Channel</sub> ≤ 400 MHz	1	1,2,3,4
В	400 MHz < BW <sub>Channel_CA</sub> ≤ 800 MHz	2	
С	800 MHz < BW <sub>Channel_CA</sub> ≤ 1200 MHz	3	1
D	200 MHz < BW <sub>Channel_CA</sub> ≤ 400 MHz	2	
E	400 MHz < BW <sub>Channel_CA</sub> ≤ 600 MHz	3	2
F	600 MHz < BW <sub>Channel_CA</sub> ≤ 800 MHz	4	
G	100 MHz < BW <sub>Channel_CA</sub> ≤ 200 MHz	2	
Н	200 MHz < BW <sub>Channel_CA</sub> ≤ 300 MHz	3	-
I	300 MHz < BW <sub>Channel_CA</sub> ≤ 400 MHz	4	-
J	400 MHz < BW <sub>Channel_CA</sub> ≤ 500 MHz	5	3
К	500 MHz < BW <sub>Channel_CA</sub> ≤ 600 MHz	6	
L	600 MHz < BW <sub>Channel_CA</sub> ≤ 700 MHz	7	-
М	700 MHz < BW <sub>Channel_CA</sub> ≤ 800 MHz	8	-
0	100 MHz ≤ BW <sub>Channel_CA</sub> ≤200 MHz	2	
Р	150 MHz ≤ BW <sub>Channel_CA</sub> ≤300 MHz	3	4
Q	200 MHz ≤ BW <sub>Channel_CA</sub> ≤ 400 MHz	4	-
MHz, 100 M NOTE 2: It is mandate fallback grou	upported component carrier bandwidths for f IHz and 100 MHz respectively except for CA ory for a UE to be able to fall back to lower o up. It is not mandatory for a UE to be able to n that belongs to a different fallback group.	bandwidth class A. rder CA bandwidth class con	figuration within a

#### Table 5.3A.4-1: CA bandwidth classes

Table 5.3A.4-2: Frequency separation classes for non-contiguous intra-band operation

Frequency separation class	Frequency separation (Fs)
I	Fs ≤ 800 MHz
II	Fs ≤ 1200 MHz
	Fs ≤ 1400 MHz

# 5.3D Channel bandwidth for UL MIMO

The requirements specified in clause 5.3 are applicable to UE supporting UL MIMO.

### 5.4 Channel arrangement

### 5.4.1 Channel spacing

#### 5.4.1.1 Channel spacing for adjacent NR carriers

The spacing between carriers will depend on the deployment scenario, the size of the frequency block available and the channel bandwidths. The nominal channel spacing between two adjacent NR carriers is defined as following:

For NR operating bands with 60 kHz channel raster,

Nominal Channel spacing =  $(BW_{Channel(1)} + BW_{Channel(2)})/2 + \{-20 \text{ kHz}, 0 \text{ kHz}, 20 \text{ kHz}\}$  for  $\Delta F_{Raster}$  equals to 60 kHz

Nominal Channel spacing =  $(BW_{Channel(1)} + BW_{Channel(2)})/2 + \{-40 \text{ kHz}, 0 \text{ kHz}, 40 \text{ kHz}\}$  for  $\Delta F_{Raster}$  equals to 120 kHz

where  $BW_{Channel(1)}$  and  $BW_{Channel(2)}$  are the channel bandwidths of the two respective NR carriers. The channel spacing can be adjusted depending on the channel raster to optimize performance in a particular deployment scenario.

### 5.4.2 Channel raster

#### 5.4.2.1 NR-ARFCN and channel raster

The global frequency raster defines a set of RF reference frequencies  $F_{REF}$ . The RF reference frequency is used in signalling to identify the position of RF channels, SS blocks and other elements.

The global frequency raster is defined for all frequencies from 0 to 100 GHz. The granularity of the global frequency raster is  $\Delta F_{Global}$ .

*RF reference frequency* is designated by an NR Absolute Radio Frequency Channel Number (NR-ARFCN) in the range [2016667...3279165] on the global frequency raster. The relation between the NR-ARFCN and the RF reference frequency  $F_{REF}$  in MHz is given by the following equation, where  $F_{REF-Offs}$  and  $N_{Ref-Offs}$  are given in Table 5.4.2.1-1 and  $N_{REF}$  is the NR-ARFCN

 $F_{REF} = F_{REF-Offs} + \Delta F_{Global} (N_{REF} - N_{REF-Offs})$ 

Table 5.4.2.1-1: NR-ARFCN parameters for the global frequency raster

Frequency range (MHz)	ΔF <sub>Global</sub> (kHz)	Fref-offs <b>(MHz)</b>	NREF-Offs	Range of NREF
24250 - 100000	60	24250.08	2016667	2016667 - 3279165

The *channel raster* defines a subset of *RF reference frequencies* that can be used to identify the RF channel position in the uplink and downlink. The *RF reference frequency* for an RF channel maps to a resource element on the carrier. For each operating band, a subset of frequencies from the global frequency raster are applicable for that band and forms a channel raster with a granularity  $\Delta F_{Raster}$ , which may be equal to or larger than  $\Delta F_{Global}$ .

The mapping between the channel raster and corresponding resource element is given in subclause 5.4.2.2. The applicable entries for each operating band are defined in subclause 5.4.2.3

#### 5.4.2.2 Channel raster to resource element mapping

The mapping between the RF reference frequency on channel raster and the corresponding resource element is given in Table 5.4.2.2-1 and can be used to identify the RF channel position. The mapping depends on the total number of RBs that are allocated in the channel and applies to both UL and DL. The mapping must apply to at least one numerology supported by the UE.

	$N_{\rm RB} \mod 2 = 0$	$N_{\rm RB} \mod 2 = 1$
Resource element index k	0	6
Physical resource block number $n_{\rm PRB}$	$n_{\rm PRB} = \left\lfloor \frac{N_{\rm RB}}{2} \right\rfloor$	$n_{\rm PRB} = \left\lfloor \frac{N_{\rm RB}}{2} \right\rfloor$

k,  $n_{\text{PRB}}$ ,  $N_{\text{RB}}$  are as defined in TS 38.211[9].

#### 5.4.2.3 Channel raster entries for each operating band

The RF channel positions on the channel raster in each NR operating band are given through the applicable NR-ARFCN in Table 5.4.2.3-1, using the channel raster to resource element mapping in subclause 5.4.2.2.

- For NR operating bands with 60 kHz channel raster above 24 GHz,  $\Delta F_{Raster} = I \times \Delta F_{Global}$ , where  $I \in \{1,2\}$ . Every  $I^{th}$  NR-ARFCN within the operating band are applicable for the channel raster within the operating band and the step size for the channel raster in Table 5.4.2.3-1 is given as  $\langle I \rangle$ .
- In frequency bands with two  $\Delta F_{Raster}$ , the higher  $\Delta F_{Raster}$  applies to channels using only the SCS that is equal to the higher  $\Delta F_{Raster}$  and the SSB SCS that is equal to or larger than the higher  $\Delta F_{Raster}$ .

Table 5.4.2.3-1: Applicable NR-ARFCN per operating band
---

Operating Band	ΔF <sub>Raster</sub> (kHz)	Uplink and Downlink Range of N <sub>REF</sub> (First – <step size=""> – Last)</step>
n257	60	2054166 - <1> - 2104165
	120	2054167 - <2> - 2104165
n258	60	2016667 - <1> - 2070832
	120	2016667 - <2> - 2070831
n260	60	2229166 - <1> - 2279165
	120	2229167 - <2> - 2279165
n261	60	2070833 - <1> - 2084999
	120	2070833 - <2> - 2084999

### 5.4.3 Synchronization raster

#### 5.4.3.1 Synchronization raster and numbering

The synchronization raster indicates the frequency positions of the synchronization block that can be used by the UE for system acquisition when explicit signalling of the synchronization block position is not present.

A global synchronization raster is defined for all frequencies. The frequency position of the SS block is defined as  $SS_{REF}$  with corresponding number GSCN. The parameters defining the  $SS_{REF}$  and GSCN for all the frequency ranges are in Table 5.4.3.1-1.

The resource element corresponding to the SS block reference frequency  $SS_{REF}$  is given in subclause 5.4.3.2. The synchronization raster and the subcarrier spacing of the synchronization block are defined separately for each band.

Frequency range	SS block frequency position SSREF	GSCN	Range of GSCN
	24250.08 MHz + N * 17.28 MHz,		
24250 – 100000 MHz		22256+ N	22256 - 26639
	N = 0: 4383		

Table 5.4.3.1-1: GSCN parameters for the global frequency raster

#### 5.4.3.2 Synchronization raster to synchronization block resource element mapping

The mapping between the synchronization raster and the corresponding resource element of the SS block is given in Table 5.4.3.2-1.

#### Table 5.4.3.2-1: Synchronization raster to SS block resource element mapping

Resource element index k	120

k is the subcarrier number of SS/PBCH block defined in TS 38.211 [9] clause 7.4.3.1.

#### 5.4.3.3 Synchronization raster entries for each operating band

The synchronization raster for each band is given in Table 5.4.3.3-1. The distance between applicable GSCN entries is given by the <Step size> indicated in Table 5.4.3.3-1.

Table 5.4.3.3-1: Applicable SS raster entries per operating band	

NR Operating Band	SS Block SCS	SS Block pattern <sup>1</sup>	Range of GSCN		
			(First – <step size=""> – Last)</step>		
n257	120 kHz	Case D	22388 - <1> - 22558		
11257	240 kHz	Case E	22390 - <2> - 22556		
n258	120 kHz	Case D	22257 - <1> - 22443		
11236	240 kHz	Case E	22258 - <2> - 22442		
n260	120 kHz	Case D	22995 - <1> - 23166		
11280	240 kHz	Case E	22996 - <2> - 23164		
n261	120 kHz	Case D	22446 - <1> - 22492		
	240 kHz	Case E	22446 - <2> - 22490		
NOTE 1: SS Block pattern is defined in subclause 4.1 in TS 38.213 [22].					

# 5.4A Channel arrangement for CA

### 5.4A.1 Channel spacing for CA

For intra-band contiguous carrier aggregation with two or more component carriers, the nominal channel spacing between two adjacent NR component carriers is defined as the following unless stated otherwise:

For NR operating bands with 60kHz channel raster:

Nominal channel spacing = 
$$\frac{BW_{Channel(1)} + BW_{Channel(2)} - 2|GB_{Channel(1)} - GB_{Channel(2)}|}{0.06 \cdot 2^{n+1}} = 0.06 \cdot 2^{n} \text{ [MHz]}$$

with

$$n=\mu_0-2$$

where BW<sub>Channel(1)</sub> and BW<sub>Channel(2)</sub> are the channel bandwidths of the two respective NR component carriers according to Table 5.3.2-1 with values in MHz,  $\mu_0$  is the largest  $\mu$  value among the subcarrier spacing configurations supported in the operating band for both of the channel bandwidths according to Table 5.3.5-1, and *GB<sub>Channel(i)</sub>* is the minimum guardband for channel bandwidth *i* according to Table 5.3.3-1 for the said  $\mu$  value, with  $\mu$  as defined in TS 38.211 [9].

The channel spacing for intra-band contiguous carrier aggregation can be adjusted to any multiple of sub-carrier spacing less than the nominal channel spacing to optimize performance in a particular deployment scenario.

For intra-band non-contiguous carrier aggregation, the channel spacing between two NR component carriers in different sub-blocks shall be larger than the nominal channel spacing defined in this subclause.

# 5.5 Configurations

# 5.5A Configurations for CA

# 5.5A.1 Configurations for intra-band contiguous CA

# Table 5.5A.1-1: NR CA configurations, bandwidth combination sets, and fallback group defined for intra-band contiguous CA

NR CA configuratio n	Uplink CA configuratio ns	BW <sub>Channel</sub> (MHz)	Maximum aggregate d BW (MHz)		Fallb ack grou p							
CA_n257B	CA_n257B	50, 100, 200, 400	400							800	0	1
CA_n257D	CA_n257D	50, 100, 200,	200							400	0	
CA_n257E	CA_n257E	50, 100, 200,	200	200						600	0	2
CA_n257F	CA_n257F	50, 100, 200,	200	200	200					800	0	
CA_n257G	CA_n257G	50, 100	100							200	0	1
CA_n257H	CA_n257H	50, 100	100	100						300	0	
CA_n257I	CA_n257I	50, 100	100	100	100					400	0	
CA_n257J	CA_n257J	50, 100	100	100	100	100				500	0	3
CA_n257K	CA_n257K	50, 100	100	100	100	100	100			600	0	
CA_n257L	CA_n257L	50, 100	100	100	100	100	100	100		700	0	4
CA_n257M	CA_n257M	50, 100	100	100	100	100	100	100	100	800	0	
CA_n260B	CA_n260B	50, 100, 200, 400	400							800	0	1
CA_n260C	CA_n260B	50, 100, 200, 400	400	400						1200	0	
CA_n260D	CA_n260D	50, 100, 200	200							400	0	2
CA_n260E	CA_n260E	50, 100, 200	200	200						600	0	
CA_n260F	CA_n260F	50, 100, 200	200	200	200					800	0	
CA_n260G	CA_n260G	50, 100	100							200	0	3
CA_n260H	CA_n260H	50, 100	100	100						300	0	
CA_n260I	CA_n260I	50, 100	100	100	100					400	0	
CA_n260J	CA_n260J	50, 100	100	100	100	100				500	0	
CA_n260K	CA_n260K	50, 100	100	100	100	100	100	400		600	0	
CA_n260L	CA_n260L	50, 100	100	100	100	100	100	100	400	700	0	
CA_n260M CA n260O	CA_n260M	50, 100	100	100	100	100	100	100	100	800	0	
CA_n2600 CA_n260P	CA_n260O CA_n260P	50, 100 50, 100	50, 100 50, 100	50 100						200	0	4
CA_1260P CA_1260Q	CA_1260P CA_n260Q	50, 100	50, 100	50, 100 50, 100	50, 100					300 400	0	4
CA_11260Q CA_11261B	CA_n261B	50, 100, 200, 400	400	30, 100	30, 100					800	0	1
CA_n261C	CA_n261B	50	400	400						850 <sup>1</sup>	0	1 '
CA_n261D	CA_n261D	50, 100, 200	200	100						400	0	2
CA_n261E	CA_n261E	50, 100, 200	200	200						600	0	
CA_n261F	CA_n261F	50, 100, 200	200	200	200					800	0	
CA_n261G	CA_n261G	50, 100	100							200	0	3
CA_n261H	CA_n261H	50, 100	100	100						300	0	<u> </u>
CA_n2611	CA_n261I	50, 100	100	100	100					400	0	1
CA_n261J	CA_n261J	50, 100	100	100	100	100				500	0	
CA_n261K	CA_n261K	50, 100	100	100	100	100	100			600	0	

NR CA configuratio n	Uplink CA configuratio ns	BW <sub>Channel</sub> (MHz)	Maximum aggregate d BW (MHz)	BCS	Fallb ack grou p							
CA_n261L	CA_n261L	50, 100	100	100	100	100	100	100		700	0	
CA_n261M	CA_n261M	50, 100	100	100	100	100	100	100	100	800	0	
CA_n261O	CA_n261O	50, 100	50, 100							200	0	
CA_n261P	CA_n261P	50, 100	50, 100	50, 100						300	0	4
CA_n261Q	CA_n261Q	50, 100	50, 100,	50, 100	50, 100					400	0	
NOTE 1: The	NOTE 1: The maximum bandwidth of band n261 is 850MHz.											
	NOTE 2: For the NR CA configuration with more than two component carries, the bandwidths in a BCS which may introduce combinations more than requested unintentionally should be listed in a row separately.											

# 5.5A.2 Configurations for intra-band non-contiguous CA

Configurations listed in this clause apply to downlink carrier aggregation only.

#### Table 5.5A.2-1: NR CA configurations with single CA bandwidth class defined for intra-band noncontiguous CA

NR configuratio n	Uplink CA configuratio ns	Sub- block	Σ(BW <sub>Chann</sub> el,block) (MHz)	BCS							
CA_n257(2A)	-	n257A	n257A							800	0
CA_n260(2A)	-	n260A	n260A							800	0
CA_n260(3A)	-	n260A	n260A	n260A						1200	0
CA_n260(4A)	-	n260A	n260A	n260A	n260A					1600	0
CA_n261(2A)	-	n261A	n261A							800	0
CA_n261(3A)	-	n261A	n261A	n261A						800	0
CA_n261(4A)	-	n261A	n261A	n261A	n261A					800	0
<ul> <li>NOTE 1: Void</li> <li>NOTE 2: Void</li> <li>NOTE 3: Void</li> <li>NOTE 4: Channel bandwidth per operating band defined in Table 5.3.5-1.</li> <li>NOTE 5: Void.</li> <li>NOTE 6: Void.</li> <li>NOTE 6: Void.</li> <li>NOTE 7: Σ(BW<sub>Channel,block</sub>) denotes the maximum total bandwidth from the summation of the sub-block bandwidths and shall be less than the bandwidth of the operating band.</li> </ul>											

## Table 5.5A.2-2: NR CA configurations and bandwidth combination sets for intra-band non-contiguous CA

CA configuration	Uplink CA configurations	Sub- block	Σ(BW <sub>Chann</sub> el,block) (MHz)	BCS						
CA_n260(A-I)	CA_n260I	n260A	CA_n26 0I						800	0
CA_n260(D-G)	CA_n260D CA_n260G	CA_n26 0D	CA_n26 0G						600	0
CA_n260(D-H)	CA_n260D CA_n260H	CA_n26 0D	CA_n26 0H						700	0
CA_n260(D-I)	CA_n260D CA_n260I	CA_n26 0D	CA_n26 0I						800	0
CA_n260(D-O)	CA_n260D CA_n260O	CA_n26 0D	CA_n26 00						600	0
CA_n260(D-P)	CA_n260D CA_n260P	CA_n26 0D	CA_n26 0P						700	0
CA_n260(D-Q)	CA_n260D CA_n260Q	CA_n26 0D	CA_n26 0Q						800	0
CA_n260(E-O)	CA_n260E CA_n260O	CA_n26 00	CA_n26 0E						800	0
CA_n260(E-P)	CA_n260E CA_n260P	CA_n26 0E	CA_n26 0P						900 <sup>1</sup>	0
CA_n260(E-Q)	CA_n260E CA_n260Q	CA_n26 0E	CA_n26 0Q						1000	0
CA_n260(G-I)	CA_n260G CA_n260I	CA_n26 0G	CA_n26 0I						600	0
CA_n261(D-G)	CA_n261D CA_n261G	CA_n26 1D	CA_n26 1G						600	0
CA_n261(D-H)									700	0

	CA_n261D	CA_n26	CA_n26						
	CA_n261H	1D	1H						
CA_n261(D-I)	CA_n261D CA_n261I	CA_n26 1D	CA_n26 1I					800	0
CA_n261(D-O)	CA_n261D CA_n261O	CA_n26 1D	CA_n26 10					600	0
CA_n261(D-P)	CA_n261D CA_n261P	CA_n26 1D	CA_n26 1P					700	0
CA_n261(D-Q)	CA_n261D CA_n261Q	CA_n26 1D	CA_n26 1Q					800	0
CA_n261(E-O)	CA_n261E CA_n261O	CA_n26 1E	CA_n26 10					800	0
CA_n261(E-P)	CA_n261E CA_n261P	CA_n26 1E	CA_n26 1P					800	0
CA_n261(E-Q)	CA_n261E CA_n261Q	CA_n26 1E	CA_n26 1Q					8001	0
NOTE 1: Void         NOTE 2: Void         NOTE 3: Unless otherwise stated, BCS0 is referred in each constituent CA configuration.         NOTE 4: Void.         NOTE 5: Void.         NOTE 6: Void.         NOTE 6: Void.         NOTE 7: Σ(BW <sub>Channel,block</sub> ) denotes the maximum total bandwidth from the summation of the sub-block bandwidths and shall be less than									

the bandwidth of the operating band.

# 5.5D Configurations for UL MIMO

The requirements specified in subclause 5.5 are applicable to UE supporting UL MIMO.

# 6 Transmitter characteristics

# 6.1 General

Editor's Note: Test configurations/environments that require new spherical scan shall be included in test procedure section and identifying such scenarios is currently FFS and owned by RAN5.

Unless otherwise stated, the transmitter characteristics are specified over the air (OTA) with a single or multiple transmit chains.

Unless otherwise stated, for power class 3 UEs, the beam correspondence side condition for SSB and CSI-RS specified in subclause 6.6.4 shall apply to the transmission tests.

Transmitter requirements for CA operation apply only when the DMRS initialization parameters (including the case when the UE applies cell ID as DMRS scrambling ID) are different across all CCs. The UE may use higher MPR values outside this limitation.

Transmitter requirements for UL MIMO operation apply when the UE transmits on 2 ports on the same CDM group. The UE may use higher MPR values outside this limitation.

For Tx test cases the identified beam peak direction can be stored and reused for a device under test in various configurations/environments for the full duration of device testing as long as beam peak direction is the same.

Unless otherwise stated, Channel Bandwidth shall be prioritized in the selecting of test points. Subcarrier spacing shall be selected after Test Channel Bandwidth is selected.

Uplink RB allocations given in Table 6.1-1 are used throughout this section, unless otherwise stated by the test case.

The UE under test shall be pre-configured with UL Tx diversity schemes disabled to account for single polarization System Simulator (SS) in the test environment. The UE under test may transmit with dual polarization.

					RB a	llocation		
Channel Bandwidt h	SCS(kHz )	OFDM	Outer_Full	Outer_1RB_Left	Outer_1RB_Right	Inner_Full (Note 1)	Inner_1RB_Left	Inner_1RB_Right
	60	DFT-s	64@0	1@0	1@65	20@22	1@22	1@43
50MHz	00	CP	66@0	1@0	1@65	22@22	1@22	1@43
3011112	120	DFT-s	32@0	1@0	1@31	10@11	1@11	1@21
	120	CP	32@0	1@0	1@31	11@11	1@11	1@21
	60	DFT-s	128@0	1@0	1@131	40@44	1@44	1@87
100MHz	00	CP	132@0	1@0	1@131	44@44	1@44	1@87
TUUNINZ	120	DFT-s	64@0	1@0	1@65	20@22	1@22	1@43
	120	CP	66@0	1@0	1@65	22@22	1@22	1@43
	60	DFT-s	256@0	1@0	1@263	81@88	1@88	1@175
200MHz	00	CP	264@0	1@0	1@263	88@88	1@88	1@175
200141112	120	DFT-s	128@0	1@0	1@131	40@44	1@44	1@87
	120	CP	132@0	1@0	1@131	44@44	1@44	1@87
	60	DFT-s	N/A	N/A	N/A	N/A	N/A	N/A
400MHz	00	CP	N/A	N/A	N/A	N/A	N/A	N/A
	120	DFT-s	256@0	1@0	1@263	64@66	1@66	1@197
	120	CP	264@0	1@0	1@263	64@66	1@66	1@197
Note 1: R	B allocation is	s left aligned	within inner	region				

# Table 6.1-1: Common Uplink Configuration PC2, for PC3 and PC4

						F	RB alloca	tion			-
Chann el Bandw idth	SCS(k Hz)	OFDM	Outer_Full	Outer_1RB_Left	Outer_1RB_Right	Inner_Full_Region1	Innner_1RB_Left_Region1	Inner_1RB_Right_Region1	Inner_Full_Region2	Innner_1RB_Left_Region2	Inner_1RB_Right_Region2
	60	DFT-s CP	64@0 66@0	1@0 1@0	1@65 1@65	20@22 23@22	1@22 1@22	1@43 1@43	32@16 33@16	1@1 1@1	1@64 1@64
50MHz		DFT-s	32@0	1@0	1@65	12@11	1@22	1@43	16@8	1@1	1@64
	120	CP	32@0	1@0	1@31	12@11	1@11	1@21	16@8	1@1	1@30
		DFT-s	128@ 0	1@0	1@13 1	45@44	1@44	1@87	64@32	1@1	1@130
100MH z	60	СР	132@ 0	1@0	1@13 1	45@44	1@44	1@87	66@33	1@1	1@130
	120	DFT-s	64@0	1@0	1@65	20@22	1@22	1@43	32@16	1@1	1@64
	120	CP	66@0	1@0	1@65	23@22	1@22	1@43	33@16	1@1	1@64
	60	DFT-s	256@ 0	1@0	1@26 3	81@88	1@88	1@175	128@6 4	1@1	1@262
200MH	00	СР	264@ 0	1@0	1@26 3	89@88	1@88	1@175	132@6 6	1@1	1@262
z	100	DFT-s	128@ 0	1@0	1@13 1	45@44	1@44	1@87	64@32	1@1	1@130
	120	СР	132@ 0	1@0	1@13 1	45@44	1@44	1@87	66@33	1@1	1@130
	60	DFT-s	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A
	00	CP	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A
400MH z	120	DFT-s	256@ 0	1@0	1@26 3	64@66	1@66	1@197	128@6 4	1@1	1@262
		СР	264@ 0	1@0	1@26 3	66@66	1@66	1@197	132@6 6	1@1	1@262
Note 1:	RB alloc	ation is le	ft aligned	within in	ner region	1 or inner	region 2 a	as defined	in clause 6	.2.2.3.1.	

#### Table 6.1-2: Common Uplink Configuration for PC1

# 6.2 Transmit power

# 6.2.1 UE maximum output power

## 6.2.1.0 General

Note: Power class 1, 2, 3, and 4 are specified based on the assumption of certain UE types with specific device architectures. The UE types can be found in Table 6.2.1.0-1.

UE Power class	UE type		
1	Fixed wireless access (FWA) UE		
2	2 Vehicular UE		
3	Handheld UE		
4	High power non-handheld UE		

Table 6.2.1.0-1: Assumption of UE Types

## 6.2.1.1 UE maximum output power - EIRP and TRP

Editor's note: The following aspects are either missing or not yet determined:

Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

- The test case is incomplete for band n259.
- Measurement Uncertainty is FFS for ETC

#### 6.2.1.1.1 Test purpose

To verify that the error of the UE maximum output power does not exceed the range prescribed by the specified nominal maximum output power and tolerance.

An excess maximum output power has the possibility to interfere to other channels or other systems. A small maximum output power decreases the coverage area.

#### 6.2.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

- 6.2.1.1.3 Minimum conformance requirements
- 6.2.1.1.3.1 UE maximum output power for power class 1

The following requirements define the maximum output power radiated by the UE for any transmission bandwidth within the channel bandwidth for non-CA configuration, unless otherwise stated. The period of measurement shall be at least one sub frame (1ms). The minimum output power values for EIRP are found in Table 6.2.1.1.3.1-1. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

Table 6.2.1.1.3.1-1: UE minimum peak EIRP for power class 1

Operating band	Min peak EIRP (dBm)		
n257	40.0		
n258	40.0		
n260	38.0		
n261	40.0		
NOTE 1: Minimum peak EIRP is defined as the lower limit without tolerance			

The maximum output power values for TRP and EIRP are found in Table 6.2.1.1.3.1-2 below. The maximum allowed EIRP is derived from regulatory requirements [8]. The requirements are verified with the test metrics of TRP (Link=TX beam peak direction, Meas=TRP grid) in beam locked mode and EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Max TRP (dBm)	Max EIRP (dBm)
n257	35	55
n258	35	55
n260	35	55
n261	35	55

The minimum EIRP at the 85<sup>th</sup> percentile of the distribution of radiated power measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 6.2.1.1.3.1-3 below. The requirement is verified with the test metric of EIRP (Link=Spherical coverage grid, Meas=Link angle).

Operati	ng band	Min EIRP at 85%-tile CDF (dBm)					
n2	57	32.0					
n2	58	32.0					
n2	60	30.0					
n2	61	32.0					
NOTE 1:		Minimum EIRP at 85%-tile CDF is defined as the lower limit without tolerance					
NOTE 2:	The requirements in this table are verified only under normal temperature conditions as defined in Annex E.2.1.						

Table 6.2.1.1.3.1-3: UE spherical coverage for power class 1

#### 6.2.1.1.3.2 UE maximum output power for power class 2

The following requirements define the maximum output power radiated by the UE for any transmission bandwidth within the channel bandwidth for non-CA configuration, unless otherwise stated. The period of measurement shall be at least one sub frame (1ms). The minimum output power values for EIRP are found in Table 6.2.1.1.3.2-1. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

 Table 6.2.1.1.3.2-1: UE minimum peak EIRP for power class 2

Operating band	Min peak EIRP (dBm)		
n257	29		
n258	29		
n261	n261 29		
NOTE 1: Minimum peak EIRP is defined as the lower limit without tolerance			

The maximum output power values for TRP and EIRP are found in Table 6.2.1.1.3.2-2 below. The maximum allowed EIRP is derived from regulatory requirements [8]. The requirements are verified with the test metrics of TRP (Link=TX beam peak direction, Meas=TRP grid) in beam locked mode and EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Max TRP (dBm)	Max EIRP (dBm)
n257	23	43
n258	23	43
n261	23	43

The minimum EIRP at the 60<sup>th</sup> percentile of the distribution of radiated power measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 6.2.1.1.3.2-3 below. The requirement is verified with the test metric of EIRP (Link=Spherical coverage grid, Meas=Link angle).

Table 6.2.1.1.3.2-3: UE	spherical coverage	e for power class 2

Operati	Operating band Min EIRP at 60%-tile CDF (dB		
n2	257 18.0		
n2	58	18.0	
n2	61	18.0	
NOTE 1:	Minimum EIRP at 60%-tile CDF is defined as the lower limit without tolerance		
NOTE 2:	under norr	equirements in this table are verified only r normal temperature conditions as ed in Annex E.2.1.	

6.2.1.1.3.3 UE maximum output power for power class 3

The following requirements define the maximum output power radiated by the UE for any transmission bandwidth within the channel bandwidth for non-CA configuration, unless otherwise stated. The period of measurement shall be at least one sub frame (1ms). The minimum output power values for EIRP are found in Table 6.2.1.1.3.2-1. The

requirement is verified with the test metric of total component of EIRP (Link=TX beam peak direction, Meas=Link angle). The requirement for the UE which supports a single FR2 band is specified in Table 6.2.1.1.3.3-1. The requirement for the UE which supports multiple FR2 bands is specified in both Table 6.2.1.1.3.3-1 and Table 6.2.1.1.3.3-4.

Operating ba	perating band Min peak EIRP (d		
n257		22.4	
n258	n258 22.4		
n259		18.7	
n260	n260 20.6		
n261		22.4	
	Minimum peak EIRP is defined as the lower limit without tolerance		
NOTE 2: Void	ł		

Table 6.2.1.1.3.3-1: UE minimum	peak EIRP for	power class 3
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The maximum output power values for TRP and EIRP are found on the Table 6.2.1.1.3.3-2. The max allowed EIRP is derived from regulatory requirements [8]. The requirements are verified with the test metrics of TRP (Link=TX beam peak direction, Meas=TRP grid) in beam locked mode and the total component of EIRP (Link=TX beam peak direction, Meas=Link angle).

Table 6.2.1.1.3.3-2: UE maximum output power limits for power class 3

Operating band	Max TRP (dBm)	Max EIRP (dBm)
n257	23	43
n258	23	43
n259	23	43
n260	23	43
n261	23	43

The minimum EIRP at the 50<sup>th</sup> percentile of the distribution of radiated power measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 6.2.1.1.3.3-3 below. The requirement is verified with the test metric of the total component of EIRP, as defined in [5] (Link=Spherical coverage grid, Meas=Link angle). The requirement for the UE which supports a single FR2 band is specified in Table 6.2.1.1.3.3-3. The requirement for the UE which supports multiple FR2 bands is specified in both Table 6.2.1.1.3.3-3 and Table 6.2.1.1.3.3-4.

Table 6.2.1.1.3.3-3: UE spherical coverage for power class 3

OI	perating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)	
	n257	11.5	
	n258	11.5	
	n259	5.8	
	n260	8	
	n261	11.5	
NOTE 1:	Minimum EIRP at 50 %-tile CDF is defined as the lower limit without tolerance		
NOTE 2:	Void		
NOTE 3:	<ol> <li>The requirements in this table are verified only under normal temperature conditions as defined in Annex E.2.1.</li> </ol>		

For the UEs that support multiple FR2 bands, minimum requirement for peak EIRP and EIRP spherical coverage in Tables 6.2.1.1.3.3-1 and 6.2.1.1.3.3-3 shall be decreased per band, respectively, by the peak EIRP relaxation parameter  $\Delta MB_{P,n}$  and EIRP spherical coverage relaxation parameter  $\Delta MB_{P,n}$ , as indicated in Table 6.2.1.1.3.3-4 to 6.2.1.1.3.3-5.

Supported bands	∑MB <sub>P</sub> (dB)	∑MBs (dB)	
n257, n258	≤ 1.3	≤ 1.25	
n257, n260	≤ 1.0	≤ 0.75 <sup>3</sup>	
n258, n260	≤ 1.0	≤ 0.75 <sup>3</sup>	
n258, n261	≤ 1.0	≤ 1.25	
n260, n261	0.0	≤ 0.75 <sup>2</sup>	
n257, n258, n260	≤ 1.7	≤ 1.75 <sup>3</sup>	
n257, n258, n261 ≤ 1.7 ≤ 1.75			
n257, n260, n261 ≤ 0.5 ≤ 1		≤ 1.25 <sup>3</sup>	
n258, n260, n261 $\leq 1.5$ $\leq 1.25^3$			
n257, n258, n260, n261	n257, n258, n260, n261 $\leq 1.7$ $\leq 1.75^3$		
NOTE 1: The requirements in this table are applicable to UEs which support only the			
indicated bands			
NOTE 2: For supported bands n260 + n261, $\Delta MB_{S,n}$ is not applied for band n260			
NOTE 3: For n260, maximum applicable $\Delta MB_{S,n}$ is 0.4 dB and $\Delta MB_{P,n}$ is 0.75 dB			
NOTE 4: For all bands except n260, the maximum applicable $\Delta MB_{P,n}$ and $\Delta MB_{S,n}$ is 0.75 dB.			

Table 6.2.1.1.3.3-4: UE multi-band relaxation factors for power class 3 (Rel-15)

Table 6.2.1.1.3.3-5: UE multi-band relaxation factors for power class 3 (Rel-16 and forward)

	Band	∆MB <sub>P,n</sub> (dB)	∆MB <sub>s,n</sub> (dB)
	n257	0.7 <sup>3</sup>	0.7 <sup>3</sup>
	n258	0.6	0.7
	n259	0.5	0.4
	n260	0.5 <sup>1</sup>	0.4 <sup>1</sup>
n261		0.5 <sup>2,4</sup>	0.74
Note 1:	Note 1: n260 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n260		
Note 2:	Note 2: n261 peak relaxation is 0 dB for UE that exclusively supports n261+n260		
Note 3:	e 3: n257 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n257		
Note 4:	Note 4: n261 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n257		

#### 6.2.1.1.3.4 UE maximum output power for power class 4

The following requirements define the maximum output power radiated by the UE for any transmission bandwidth within the channel bandwidth for non-CA configuration, unless otherwise stated. The period of measurement shall be at least one sub frame (1ms). The minimum output power values for EIRP are found in Table 6.2.1.1.3.4-2. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Min peak EIRP (dBm)	
n257	34	
n258	34	
n260	31	
n261	34	
NOTE 1: Minimum peak EIRP is defined as the		
lower limit without tolerance		

Table 6.2.1.1.3.4-1: UE minimum peak EIRP for power class 4

The maximum output power values for TRP and EIRP are found in Table 6.2.1.1.3.4-2 below. The maximum allowed EIRP is derived from regulatory requirements [8]. The requirements are verified with the test metrics of TRP (Link=TX beam peak direction, Meas=TRP grid) in beam locked mode and EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Max TRP (dBm)	Max EIRP (dBm)
n257	23	43
n258	23	43
n260	23	43
n261	23	43

Table 6.2.1.1.3.4-2: UE maximum out	put power limits for power class 4

The minimum EIRP at the 20<sup>th</sup> percentile of the distribution of radiated power measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 6.2.1.1.3.4-3 below. The requirement is verified with the test metric of EIRP (Link=Spherical coverage grid, Meas=Link angle).

Table 6.2.1.1.3.4-3: UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)			
n257	25			
n258	25			
n260	19			
n261	25			
	Minimum EIRP at 20%-tile CDF is defined as the lower limit without tolerance			
under norr	he requirements in this table are verified only nder normal temperature conditions as efined in Annex E.2.1.			

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.1.

6.2.1.1.4 Test description

#### 6.2.1.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Default Conditions							
Test Environment as specified in TS 38.508-1 [10]			Normal, TL/VL, TL/VH, TH/VL, TH/VH				
subclau	use [4.1]		-	-	(NOTE 2)		
		as specifie	ed in TS 38.508-1 [′	10]	Low range, Mid R	ange, High range	
subclau	use [4.3.1]						
Test Ch	nannel Ban	dwidths as	s specified in TS		Lowest, 100 MHz	, Highest	
38.508	-1 [10] subo	clause [4.3	3.1]				
Test SO	Test SCS as specified in Table 5.3.5-1 120 kHz						
			Test P	aram	eters		
Test	ChBw	SCS	Downlink		Uplink C	onfiguration	
ID			Configuration				
		Default	N/A	Modulation		RB allocation (NOTE 1)	
1	50			DF	T-s-OFDM QPSK	Inner_Full for PC2, PC3	
2	100					and PC4	
3	200					Inner_Full_Region1 for	
4	400					PC1	
NOTE	1: The spe	ecific confi	guration of each RF	= allo	cation is defined in	Table 6.1-1 for PC2, PC3	
	and PC	4 or Table	6.1-2 for PC1.				
NOTE 2	2: Test en	vironment	for UE Max TRP is	norr	nal only.		

Table 6.2.1.1.4.1-1:	Test Co	onfiguration	Table
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- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2.1.1.4.3

#### 6.2.1.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.2.1.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2.1.1.4.3.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec starting from the first TPC command in this step to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Tables 6.2.1.1.5-1 to 6.2.1.1.5-4. EIRP test procedure is defined in Annex K.1.3. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 6. Measure TRP of the transmitted signal for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.5.2.3.5-1. Total radiated power is measured according to TRP measurement procedure defined in Annex K.1.7 and measurement grid specified in Annex M.4. TRP is calculated considering both polarizations, theta and phi.
- 7. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2.1.1.5 Test requirement

The EIRP derived in step 4 and TRP derived in step 5 shall not exceed the values specified in Table 6.2.1.1.5-1 to Table 6.2.1.1.5-4.

Operating band	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
n257	35+TT	55	40.0-TT
n258	35+TT	55	40.0-TT
n260	35+TT	55	38.0-TT
n261	35+TT	55	40.0-TT

 Table 6.2.1.1.5-1: UE maximum output test requirements for power class 1

Table 6.2.1.1.5-2: UE maximum output test requirements for power class 2

Operating band	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
n257	23+TT	43	29-TT
n258	23+TT	43	29-TT
n260			
n261	23+TT	43	29-TT

Table 6.2.1.1.5-3: UE maximum output test requirements for power class 3 for single band UE or multiband UE declaring  $MB_p = 0$  in all FR2 bands

Operating band	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
n257	23+TT	43	22.4-TT
n258	23+TT	43	22.4-TT
n260	23+TT	43	20.6-TT
n261	23+TT	43	22.4-TT

ID	Supported FR2 bands set		Test requii (No	Maximum sum of MB <sub>p</sub> , ∑MB <sub>P</sub> (dB) (Note 3)	Comments		
		n257	n258	n260	n261		
1	n257, n258	22.4-TT-MB <sub>p</sub>	22.4-TT-MB <sub>p</sub>			1.3	Maximum 0.75 dB relaxation allowed for each band
2	n257, n260	22.4-TT-MB <sub>p</sub>		20.6-TT-MB <sub>p</sub>		1.0	Maximum 0.75 dB relaxation allowed for each band
3	n258, n260		22.4-TT-MBp	20.6-TT-MB <sub>p</sub>		1.0	Maximum 0.75 dB relaxation allowed for each band
4	n258, n261		22.4-TT-MB <sub>p</sub>		22.4-TT-MB <sub>p</sub>	1.0	Maximum 0.75 dB relaxation allowed for each band
5	n260, n261					0.0	No relaxation factor allowed
6	n257, n258, n260	22.4-TT-MB <sub>p</sub>	22.4-TT-MB <sub>p</sub>	20.6-TT-MB <sub>p</sub>		1.7	Maximum 0.75 dB relaxation allowed for each band
7	n257, n258, n261	22.4-TT-MB <sub>p</sub>	22.4-TT-MBp		22.4-TT-MBp	1.7	Maximum 0.75 dB relaxation allowed for each band
8	n257, n260, n261	22.4-TT-MB <sub>p</sub>		20.6-TT-MB <sub>p</sub>	22.4-TT-MBp	0.5	Maximum 0.75 dB relaxation allowed for each band
9	n258, n260, n261		22.4-TT-MB <sub>p</sub>	20.6-TT-MB <sub>p</sub>	22.4-TT-MB <sub>p</sub>	1.5	Maximum 0.75 dB relaxation allowed for each band
10	n257, n258, n260, n261	22.4-TT-MB <sub>p</sub>	22.4-TT-MB <sub>p</sub>	20.6-TT-MB <sub>p</sub>	22.4-TT-MB <sub>p</sub>	1.7	Maximum 0.75 dB relaxation allowed for each band
Note 2 Note 2 Note 2 Note 2	This declaration sh 2: All UE supported b 3: Max allowed sum of	all fulfil the requ ands needs to b of MB <sub>P</sub> over all s	irements in Ta be tested to en upported FR2	ble 6.2.1.1.3.3 sure the multib bands as defir	9-4. band relaxation on thed in clause 6.2	declaration is c 2.1.1.3.3.	ompliant

# Table 6.2.1.1.5-3a: UE maximum output test requirements for power class 3 for multi band UE declaring $MB_p>0$ in any FR2 band (Rel-15)

## Table 6.2.1.1.5-3b: Test Tolerance (Max TRP for Power class 3)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.65 dB	2.77 dB

## Table 6.2.1.1.5-3c: Test Tolerance (Min peak EIRP for Power class 3)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.87 dB	2.87 dB

ID	FR2 bands/set	Test requirement (dB) (Note 1)					Comments
		n257	n258	n259	n260	n261	
1	n257	22.4-TT-∆MB <sub>P,n</sub>					
2	n258		22.4-TT- $\Delta MB_{P,n}$				
3	n259			18.7-TT-∆MB <sub>P,n</sub>			
4	n260				20.6-TT-∆MB <sub>P,n</sub>		
5	n261					22.4-TT-∆MB <sub>P,n</sub>	
6	n257, n261	$22.4\text{-}TT\text{-}\Delta MB_{P,n}$				22.4-TT- $\Delta MB_{P,n}$	$\Delta MB_{P,n}$ relaxation is 0 dB
7	n260, n261				20.6-TT-∆MB <sub>P,n</sub>		$\Delta MB_{P,n}$ relaxation is 0 dB

#### Table 6.2.1.1.5-3d: UE maximum output test requirements for power class 3 (Rel-16 and forward)

#### Table 6.2.1.1.5-4: UE maximum output power test requirements for power class 4

Operating band	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
n257	23+TT	43	34-TT
n258	23+TT	43	34-TT
n260	23+TT	43	31-TT
n261	23+TT	43	34-TT

### 6.2.1.2 UE maximum output power - Spherical coverage

Editor's note: The following aspects are either missing or not yet determined:

Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2.1.2.1 Test purpose

To verify that the spatial coverage of the UE in expected directions is acceptable.

#### 6.2.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that support beam correspondence without UL beam sweeping.

#### 6.2.1.2.3 Minimum conformance requirements

Minimum conformance requirements are defined in clause 6.2.1.1.3.

6.2.1.2.4 Test description

#### 6.2.1.2.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2.1.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Default Conditions					
Test Er	nvironment	as specifie	ed in TS 38.508-1 [	10]	Normal	
subclau	use [4.1]					
Test Fr	equencies	as specifie	ed in TS 38.508-1 [′	10]	Low range, Mid R	ange, High range
subclau	use [4.3.1]					
Test Ch	nannel Ban	dwidths as	s specified in TS		Lowest, Highest	
	-1 [10] subo					
Test SO	CS as spec	ified in Tal	ble 5.3.5-1		120 kHz	
			Test P	aram	eters	
Test	ChBw	SCS	Downlink		Uplink C	onfiguration
ID			Configuration			
		Default	N/A		Modulation	<b>RB allocation (NOTE 1)</b>
1	50			DF	T-s-OFDM QPSK	Inner_Full for PC2, PC3
2	100					and PC4
3	200					Inner_Full_Region1 for
4 400						PC1
NOTE	1: The spe	ecific confi	guration of each RI	= allo	cation is defined in	Table 6.1-1 for PC2, PC3
	and PC	4 or Table	6.1-2 for PC1.			

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2.1.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2.1.2.4.3

#### 6.2.1.2.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.2.1.2.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2.1.2.4.3.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 4. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP measurements for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.3. After a rotation, allow TBD ms for UE to find the best beam to use. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 5. Calculate a cumulative distribution function for the measured EIRP values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2.1.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2.1.2.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 5 shall exceed the values specified in Table 6.2.1.2.5-1 to Table 6.2.1.2.5-4.

Table 6.2.1.2.5-1: UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
n257	32.0-TT
n258	32.0-TT
n260	30.0-TT
n261	32.0-TT

#### Table 6.2.1.2.5-2: UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)
n257	18.0-TT
n258	18.0-TT
n260	
n261	18.0-TT

# Table 6.2.1.2.5-3: UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)
n257	11.5-TT
n258	11.5-TT
n259	5.8-TT
n260	8-TT
n261	11.5-TT

ID	Supported FR2 bands set		Test requir (Not		Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		n257	n258	n260	n261		
1	n257, n258	11.5-TT-MBs	11.5-TT-MBs			1.25	Maximum 0.75 dB relaxation allowed for each band
2	n257, n260	11.5-TT-MBs		8-TT-MB₅		0.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
3	n258, n260		11.5-TT-MB₅	8-TT-MB₅		0.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
4	n258, n261		11.5-TT-MBs		11.5-TT-MB₅	1.25	Maximum 0.75 dB relaxation allowed for each band
5	n260, n261			8-TT-MB₅	11.5-TT-MBs	0.75	No relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
6	n257, n258, n260	11.5-TT-MBs	11.5-TT-MB₅	8-TT-MB₅		1.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
7	n257, n258, n261	11.5-TT-MBs	11.5-TT-MB <sub>s</sub>		11.5-TT-MBs	1.75	Maximum 0.75 dB relaxation allowed for each band
8	n257, n260, n261	11.5-TT-MBs		8-TT-MB₅	11.5-TT-MBs	1.25	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
9	n258, n260, n261		11.5-TT-MBs	8-TT-MB₅	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
10	n257, n258, n260, n261	11.5-TT-MB <sub>s</sub>	11.5-TT-MB₅	8-TT-MB₅	11.5-TT-MB <sub>s</sub>	1.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands
Note 2 Note 2 Note 3 Note 4	declaration shall fu 2: All UE supported b 3: Max allowed sum of	Ifil the requirement ands needs to b of MB <sub>s</sub> over all s	ents in Table 6 be tested to ens upported FR2 b	2.1.1.3.3-4. sure the multit bands as defir	band relaxation on the contract of the contrac	declaration is c 2.1.1.3.3.	

# Table 6.2.1.2.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB<sub>s</sub>>0 in any FR2 band (Rel-15)

Table 6.2.1.2.5-3b: Test Tolerance (UE spherical coverage for Power class 3)

Test Metric	FR2a	FR2b	
Quiet Zone size ≤ 30 cm	2.58 dB	2.58 dB	

ID	FR2 bands/set	Test requirement (dB) (Note 1)					Comments
		n257	n258	n259	n260	n261	
1	n257	22.4-TT- $\Delta MB_{s,n}$					
2	n258		22.4-TT-∆MB <sub>s,n</sub>				
3	n259			18.7-TT-∆MB <sub>s,n</sub>			
4	n260				20.6-TT-∆MB <sub>s,n</sub>		
5	n261					22.4-TT-∆MB <sub>s,n</sub>	
6	n257, n261	22.4-TT- $\Delta MB_{s,n}$				$22.4\text{-}TT\text{-}\Delta MB_{s,n}$	$\Delta MB_{s,n}$ relaxation is 0 dB
7	n260, n261				$20.6\text{-}TT\text{-}\Delta MB_{s,n}$	22.4-TT- $\Delta MB_{s,n}$	$\Delta MB_{s,n}$ relaxation is 0 dB for n260
Note	1: $\Delta MB_{s,n}$ is the	Multiband Relaxa	ation factor for the	tested band. This	shall fulfil the requ	uirements in Table	e 6.2.1.1.3.3-5.

#### Table 6.2.1.2.5-3c: UE spherical coverage for power class 3 (Rel-16 and forward)

Operating band	Min EIRP at 20%-tile CDF (dBm)
n257	25
n258	25
n260	19
n261	25

# 6.2.2 UE maximum output power reduction

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are FFS for PC1, PC2 and PC4.
- Measurement grid for PC2/4 in Annex M.4 is FFS.
- Measurment with *modifiedMPRbehavior* is FFS.

#### 6.2.2.0 General

The requirements in section 6.2.2 only apply when both UL and DL of a UE are configured for single CC operation, and they are of the same bandwidth. A UE may reduce its maximum output power due to modulation orders, transmit bandwidth configurations, waveform types and narrow allocations. This Maximum Power Reduction (MPR) is defined in subclauses below. The allowed MPR for SRS, PUCCH formats 0, 1, 3 and 4, and PRACH shall be as specified for QPSK modulated DFT-s-OFDM of equivalent RB allocation. The allowed MPR for PUCCH format 2 shall be as specified for QPSK modulated CP-OFDM of equivalent RB allocation. When the maximum output power of a UE is modified by MPR, the power limits specified in subclause 6.2.4 apply.

For a UE that is configured for single CC operation with different channel bandwidths in UL and DL, the requirements in section 6.2A.2 apply.

For all power classes, the waveform defined by BW = 100 MHz, SCS = 120 kHz, DFT-S-OFDM QPSK, 20RB23 is the reference waveform with 0 dB MPR and is used for the power class definition.

#### 6.2.2.1 Test purpose

The number of RB identified in 6.2.2.3 is based on meeting the requirements for the maximum power reduction (MPR) due to Cubic Metric (CM).

#### 6.2.2.2 Test applicability

The requirements of this test apply to all types of NR UE release 15 and forward.

#### 6.2.2.3 Minimum conformance requirements

#### 6.2.2.3.1 UE maximum output power reduction for power class 1

For power class 1, MPR for contiguous allocations is defined as:

$$MPR = max(MPR_{WT}, MPR_{narrow})$$

Where,

 $MPR_{narrow} = 14.4 \text{ dB}$ , when  $BW_{alloc,RB} \le 1.44 \text{ MHz}$ ,  $MPR_{narrow} = 10 \text{ dB}$ , when  $1.44 \text{ MHz} < BW_{alloc,RB} \le 10.8 \text{ MHz}$ , where  $BW_{alloc,RB}$  is the bandwidth of the RB allocation size.

 $MPR_{WT}$  is the maximum power reduction due to modulation orders, transmission bandwidth configurations listed in table 5.3.2-1, and waveform types.  $MPR_{WT}$  is defined in Tables 6.2.2.3.1-1 and 6.2.2.3.1-2.

Table 6.2.2.3.1-1: MPR<sub>WT</sub> for power class 1, BW<sub>channel</sub> ≤ 200 MHz

		MPR <sub>w</sub> т (dB), BW <sub>channel</sub> ≤ 200 MHz				
Modulation		Outer RB allocations	Inner RB al	locations		
			Region 1	Region 2		
	Pi/2 BPSK	≤ 5.5	0.0	≤ 3.0		
DFT-s-OFDM	QPSK	≤ 6.5	0.0	≤ 3.0		
DF1-S-OFDM	16 QAM	≤ 6.5	≤ 4.0	≤ 4.0		
	64 QAM	≤ 6.5	≤ 5.0	≤ 5.0		
	QPSK	≤ 7.0	≤ 4.5	≤ 4.5		
CP-OFDM	16 QAM	≤ 7.0	≤ 5.5	≤ 5.5		
	64 QAM	≤ 7.5	≤ 7.5	≤ 7.5		

Table 6.2.2.3.1-2: MPR<sub>WT</sub> for power class 1, BW<sub>channel</sub> = 400 MHz

		MPR <sub>WT</sub> (dB), BW <sub>channel</sub> = 400 MHz				
Modulation		Outer RB allocations	Inner RB allocations			
			Region 1	Region 2		
	Pi/2 BPSK	≤ 5.5	0.0	≤ 3.0		
DFT-s-OFDM	QPSK	≤ 6.5	0.0	≤ 3.5		
DF1-S-OFDM	16 QAM	≤ 6.5	≤ 4.5	≤ 4.5		
	64 QAM	≤ 6.5	≤ 6.5	≤ 6.5		
	QPSK	≤ 7.0	≤ 5.0	≤ 5.0		
CP-OFDM	16 QAM	≤ 7.0	≤ 6.5	≤ 6.5		
	64 QAM	≤ 9.0	≤ 9.0	≤ 9.0		

Where the following parameters are defined to specify valid RB allocation ranges for the RB allocations regions in Tables 6.2.2.3.1-1 and 6.2.2.3.1-2:

N<sub>RB</sub> is the maximum number of RBs for a given Channel bandwidth and sub-carrier spacing defined in Table 5.3.2-1.

$$RB_{end} = RB_{Start} + L_{CRB} - 1$$

$$RB_{Start,Low} = Max(1, Floor(L_{CRB}/2))$$

where Max() indicates the largest value of all arguments and Floor(x) is the greatest integer less than or equal to x.

$$RB_{Start,High} = N_{RB} - RB_{Start,Low} - L_{CRB}$$

An RB allocation is an Outer RB allocation if

RB<sub>Start</sub> < RB<sub>Start,Low</sub> OR RB<sub>Start</sub> > RB<sub>Start,High</sub> OR L<sub>CRB</sub> > Ceil(N<sub>RB</sub>/2)

where Ceil(x) is the smallest integer greater than or equal to x.

An RB allocation belonging to Table 6.2.2.3.1-1 is a Region 1 inner RB allocation if

 $RB_{start} \ge Ceil(1/3 N_{RB}) AND RB_{end} < Ceil(2/3 N_{RB})$ 

An RB allocation belonging to Table 6.2.2.3.1-2 is a Region 1 inner RB allocation if

 $RB_{start} \ge Ceil(1/4 N_{RB}) \text{ AND } RB_{end} < Ceil(3/4 N_{RB}) \text{ AND } L_{CRB} \le Ceil(1/4 N_{RB})$ 

An RB allocation is a Region 2 inner allocation if it is NOT an Outer allocation AND NOT a Region 1 inner allocation.

For the UE maximum output power modified by MPR, the power limits specified in subclause 6.2.4 apply.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.2.1.

#### 6.2.2.3.2 UE maximum output power reduction for power class 2

For power class 2, MPR specified in subclause 6.2.2.3.3 applies.

#### Table 6.2.2.3.2-1: Void

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.2.2.

#### 6.2.2.3.3 UE maximum output power reduction for power class 3

For power class 3, MPR for contiguous allocations is defined as:

$$MPR = max(MPR_{WT}, MPR_{narrow})$$

Where,

$$\begin{split} MPR_{narrow} = 2.5 \text{ dB}, BW_{alloc,RB} \leq 1.44 \text{ MHz}, \text{ and } 0 \leq RB_{start} < Ceil(1/3 \text{ } N_{RB}) \text{ or } Ceil(2/3N_{RB}) \leq RB_{start} \leq N_{RB}\text{-}L_{CRB}, \\ \text{where } BW_{alloc,RB} \text{ is the bandwidth of the RB allocation size}. \end{split}$$

MPR<sub>WT</sub> is the maximum power reduction due to modulation orders, transmission bandwidth configurations listed in Table 5.3.2-1, and waveform types. MPR<sub>WT</sub> is defined in Table 6.2.2.3.3-1 and Table 6.2.2.3.3-2.

Table 6.2.2.3.3-1: MPR<sub>WT</sub> for power class 3, BWchannel ≤ 200 MHz

		MPRwt, BW <sub>channel</sub> ≤ 200 MHz		
Modula	tion	Inner RB allocations, Region 1	Edge RB allocations	
	Pi/2 BPSK	0.0	≤ 2.0	
DFT-s-OFDM	QPSK	0.0	≤ 2.0	
DF1-S-OFDIVI	16 QAM	≤ 3.0	≤ 3.5	
	64 QAM	≤ 5.0	≤ 5.5	
	QPSK	≤ 3.5	≤ 4.0	
CP-OFDM	16 QAM	≤ 5.0	≤ 5.0	
	64 QAM	≤ 7.5	≤ 7.5	

Table 6.2.2.3.3-2: MPR <sub>WT</sub> for	power class 3, E	SW <sub>channel</sub> = 400 MHz
--	------------------	---------------------------------

		MPR <sub>WT</sub> , BW <sub>channel</sub> = 400 MHz		
Modula	tion	Inner RB allocations, Region 1	Edge RB allocations	
	Pi/2 BPSK	0.0	≤ 3.0	
DFT-s-OFDM	QPSK	0.0	≤ 3.0	
DF1-S-OFDIVI	16 QAM	≤ 4.5	≤ 4.5	
	64 QAM	≤ 6.5	≤ 6.5	
	QPSK	≤ 5.0	≤ 5.0	
CP-OFDM	16 QAM	≤ 6.5	≤ 6.5	
	64 QAM	≤ 9.0	≤ 9.0	

Where the following parameters are defined to specify valid RB allocation ranges for RB allocations in Tables 6.2.2.3.3-1 and 6.2.2.3.3-2:

N<sub>RB</sub> is the maximum number of RBs for a given Channel bandwidth and sub-carrier spacing defined in Table 5.3.2-1.

$$\mathbf{RB}_{\mathrm{end}} = \mathbf{RB}_{\mathrm{Start}} + \mathbf{L}_{\mathrm{CRB}} - 1$$

An RB allocation belonging to table 6.2.2.3.3-1 is a Region 1 inner RB allocation if

$$RB_{start} \ge Ceil(1/3 N_{RB}) AND RB_{end} < Ceil(2/3 N_{RB})$$

An RB allocation belonging to table 6.2.2.3.3-2 is a Region 1 inner RB allocation if

$$RB_{start} \ge Ceil(1/4 N_{RB}) AND RB_{end} < Ceil(3/4 N_{RB}) AND L_{CRB} \le Ceil(1/4 N_{RB})$$

An RB allocation is an Edge allocation if it is NOT a Region 1 inner allocation.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.2.3.

#### 6.2.2.3.4 UE maximum output power reduction for power class 4

For power class 4, MPR specified in sub-clause 6.2.2.3.3 applies.

#### Table 6.2.2.3.4-1: Void

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.2.4.

6.2.2.4 Test description

6.2.2.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in Table 6.2.2.4.1-1 to Table 6.2.2.4.1-9. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Default Conditions						
		ent as spe	cified in T	S 38.508-1 [10]	Normal		
subcla	use 4.1						
	•	•	cified in TS	S 38.508-1 [10]	Low range, High range		
subcla	use 4.3.1						
		Bandwidths		fied in TS	Lowest and Highest		
		ubclause 4					
Test S	CS as sp	pecified in	Table 5.3		120kHz		
	Test Parameters						
Test	Freq	ChBw	SCS	Downlink	Uplink Configuration		
ID				Configuration			
				N/A for	Modulation	RB allocation	
				Maximum		(NOTE 1)	
1	Low	Default	Default	Power	CP-OFDM 64 QAM	Outer_1RB_Left	
2	High	Delaun	Delaun	Reduction	CP-OFDM 64 QAM	Outer_1RB_Right	
				(MPR) test			
				case			
3	Low				CP-OFDM 64 QAM	2@0	
4	High				CP-OFDM 64 QAM	2@N <sub>RB</sub> -2	
5	Low				CP-OFDM 64 QAM	7@0	
6	High				CP-OFDM 64 QAM	7@N <sub>RB</sub> -7	
NOTE	1: The	specific co	onfiguratio	n of each RF allo	cation is defined in Table 6	.1-2.	

	Default Conditions							
Test E	Invironme	nt as spec	cified in TS	Normal				
	ause 4.1							
	requencie	es as spec	ified in TS	Low range, High range	9			
	ause 4.3.1							
	Channel Ba			ied in TS	Lowest and Highest su			
	8-1 [10] su				bandwidth that ≤ 200 M	MHz		
Test S	SCS as sp	ecified in	Table 5.3.		120kHz			
<b>T</b> 1	-		000	Test Parame		<u>.</u>		
Test ID	Freq	ChBw	SCS	Downlink	Uplink Con	figuration		
שו				Configuration		RB allocation		
					Modulation	(NOTE 1)		
1	Low				DFT-s-OFDM PI/2	8@0		
					BPSK			
2	High				DFT-s-OFDM PI/2	8@N <sub>RB</sub> -8		
	Defeult				BPSK	Outer Full		
3	Default				DFT-s-OFDM PI/2 BPSK	Outer_Full		
4	Default				DFT-s-OFDM QPSK	Inner_Full_Region2		
5	Default				DFT-s-OFDM QF3K	Inner_Full_Region2		
5	Delault				QAM	Inner_run_rtegionz		
6	Low			N/A for	DFT-s-OFDM 64	8@0		
Ū,				Maximum	QAM			
7	High	Default	Default	Power	DFT-s-OFDM 64	8@N <sub>RB</sub> -8		
	Ũ			Reduction	QAM			
8	Default			(MPR) test	DFT-s-OFDM 64	Outer_Full		
				case	QAM			
9	Default				DFT-s-OFDM 64	Inner_Full_Region2		
					QAM			
10	Default				CP-OFDM QPSK	Inner_Full_Region2		
11	Low				CP-OFDM 16 QAM	8@0		
12	High				CP-OFDM 16 QAM	8@N <sub>RB</sub> -8		
13	Default				CP-OFDM 16 QAM	Outer_Full		
14	Default				CP-OFDM 16 QAM	Inner_Full_Region2		
15	Low				CP-OFDM 64 QAM	8@0		
16	High				CP-OFDM 64 QAM	8@N <sub>RB</sub> -8		
17	Default		<i>c</i>		CP-OFDM 64 QAM	Outer_Full		
NOTE 1: The specific configuration of each RF allocation is defined in clause 6.1-2.								

# Table 6.2.2.4.1-2: Test Configuration Table (Power Class 1, MPR<sub>WT</sub>, BWchannel ≤ 200 MHz)

	Default Conditions							
		nt as spec	ified in TS	38.508-1 [10]	Normal			
	use 4.1		·/· · · · · · · · · · · · · · · · · · ·	00 500 4 [40]				
	requencie ause 4.3.1	es as spec	ified in TS	38.508-1 [10]	Low range, High range			
	Channel Ba	andwidths	as specifi	ied in TS	400 MHz			
	3-1 [10] su				400 10112			
	SCS as sp			5-1	120kHz			
				Test Parame	eters			
Test	Freq	ChBw	SCS	Downlink	Uplink Con	figuration		
ID				Configuration				
					Modulation	RB allocation (NOTE 1)		
1	Low				DFT-s-OFDM PI/2 BPSK	8@0		
2	High				DFT-s-OFDM PI/2 BPSK	8@N <sub>RB</sub> -8		
3	Default				DFT-s-OFDM PI/2 BPSK	Outer_Full		
4	Default				DFT-s-OFDM PI/2 BPSK	Inner_Full_Region2		
5	Default				DFT-s-OFDM QPSK	Inner_Full_Region2		
6	Default			N/A for Maximum	DFT-s-OFDM 16 QAM	Inner_Full_Region2		
7	Low	Default	Default	Power Reduction	DFT-s-OFDM 64 QAM	8@0		
8	High			(MPR) test case	DFT-s-OFDM 64 QAM	8@N <sub>RB</sub> -8		
9	Default				DFT-s-OFDM 64 QAM	Outer_Full		
10	Default				CP-OFDM QPSK	Inner_Full_Region2		
11	Low				CP-OFDM 16 QAM	8@0		
12	High				CP-OFDM 16 QAM	8@N <sub>RB</sub> -8		
13	Default				CP-OFDM 16 QAM	Outer_Full		
14	Default				CP-OFDM 16 QAM	Inner_Full_Region2		
15	Low				CP-OFDM 64 QAM	8@0		
16	High				CP-OFDM 64 QAM	8@N <sub>RB</sub> -8		
17	Default				CP-OFDM 64 QAM	Outer_Full		
NOTE	NOTE 1: The specific configuration of each RF allocation is defined in clause 6.1-2.							

## Table 6.2.2.4.1-3: Test Configuration Table (Power Class 1, MPR<sub>WT</sub>, BWchannel = 400 MHz)

Table 6.2.2.4.1-4: Void

Table 6.2.2.4.1-5: Void

Table 6.2.2.4.1-6: Void

## Table 6.2.2.4.1-7: Test Configuration Table (Power Class 2, 3 and 4, MPR<sub>narrow</sub>, BWchannel ≤ 200 MHz)

Default Conditions						
Test E	Invironme	ent as spe	cified in T	S 38.508-1 [10]	Normal	
subclause 4.1						
Test F	requenci	es as spe	cified in TS	S 38.508-1 [10]	Low range, High range	
subcla	ause 4.3.1	1				
Test C	Channel E	Bandwidth	s as specit	fied in TS	Lowest and Highes supp	
38.50	8-1 [10] s	ubclause	4.3.1		bandwidth that ≤ 200 MH	lz t
Test S	SCS as sp	pecified in	Table 5.3	.5-1	120kHz	
				Test Param	eters	
Test	Freg ChBw SCS Downlink					
1631	⊢req	ChBw	SCS	Downlink	Uplink Config	guration
ID	Freq	ChBw	SCS	Downlink Configuration	Uplink Config	guration
	Freq	ChBw	SCS			guration RB allocation
	Freq	ChBw	SCS	Configuration	Uplink Config Modulation	-
	Low			Configuration N/A for		RB allocation
ID		<b>ChBw</b> Default	SCS Default	Configuration N/A for Maximum	Modulation	RB allocation (NOTE 1)
<b>ID</b>	Low			Configuration N/A for Maximum Power	Modulation DFT-s-OFDM QPSK	RB allocation (NOTE 1) Outer_1RB_Left
<b>ID</b>	Low			Configuration N/A for Maximum Power Reduction	Modulation DFT-s-OFDM QPSK	RB allocation (NOTE 1) Outer_1RB_Left

## Table 6.2.2.4.1-8: Test Configuration Table (Power Class 2, 3 and 4, MPR<sub>wT</sub>, BWchannel ≤ 200 MHz)

	Default Conditions							
Test Environment as specified in TS 38.508-1 [10]					Normal			
	ause 4.1							
Test Frequencies as specified in TS 38.508-1 [10]					Low range, High range			
subclause 4.3.1								
	Channel Ba			Lowest and Highest sup				
	3-1 [10] su				bandwidth that ≤ 200 MH	lz		
Test S	SCS as sp	ecified in T	Table 5.3.		120kHz			
				Test Parame		-		
Test	Freq	ChBw	SCS	Downlink	Uplink Confi	guration		
ID				Configuration				
					Modulation	RB allocation (NOTE 1)		
1	Default				DFT-s-OFDM QPSK	Outer_Full		
2	Default				DFT-s-OFDM 16 QAM	Inner_Full		
3	Low				DFT-s-OFDM 16 QAM	Outer_1RB_Left		
4	High				DFT-s-OFDM 16 QAM	Outer_1RB_Right		
5	Default				DFT-s-OFDM 16 QAM	Outer_Full		
6	Default			N/A for	DFT-s-OFDM 64 QAM	Inner_Full		
7	Low			Maximum	DFT-s-OFDM 64 QAM	Outer_1RB_Left		
8	High			Power	DFT-s-OFDM 64 QAM	Outer_1RB_Right		
9	Default	Default	Default	Reduction	DFT-s-OFDM 64 QAM	Outer_Full		
10	Default			(MPR) test case	CP-OFDM QPSK	Inner_Full		
11	Low				CP-OFDM QPSK	Outer_1RB_Left		
12	High			0000	CP-OFDM QPSK	Outer_1RB_Right		
13	Default				CP-OFDM QPSK	Outer_Full		
14	Low				CP-OFDM 16 QAM	Outer_1RB_Left		
15	High				CP-OFDM 16 QAM	Outer_1RB_Right		
16	Default				CP-OFDM 16 QAM	Outer_Full		
17	Low				CP-OFDM 64 QAM	Outer_1RB_Left		
18	High				CP-OFDM 64 QAM	Outer_1RB_Right		
19	Default				CP-OFDM 64 QAM	Outer_Full		
NOTE	NOTE 1: The specific configuration of each RF allocation is defined in Table 6.1-1.							

	Default Conditions							
Test Environment as specified in TS 38.508-1 [10]					Normal			
subclause 4.1								
Test Frequencies as specified in TS 38.508-1 [10]					Low range, High range			
subclause 4.3.1								
Test Channel Bandwidths as specified in TS					400 MHz			
	8-1 [10] su							
Test S	SCS as sp	ecified in <sup>-</sup>	Table 5.3.	5-1	120kHz			
				Test Parame				
Test	Freq	ChBw	SCS	Downlink	Uplink Config	guration		
ID				Configuration				
					Modulation	RB allocation (NOTE 1)		
1	Low				DFT-s-OFDM QPSK	Outer_1RB_Left		
2	High			İ	DFT-s-OFDM QPSK	Outer_1RB_Right		
3	Default				DFT-s-OFDM QPSK	Outer_Full		
4	Low				DFT-s-OFDM 16 QAM	Outer_1RB_Left		
5	High				DFT-s-OFDM 16 QAM	Outer_1RB_Right		
6	Default			N/A for	DFT-s-OFDM 16 QAM	Outer_Full		
7	Low			Maximum	DFT-s-OFDM 64 QAM	Outer_1RB_Left		
8	High	Default	Default	Power	DFT-s-OFDM 64 QAM	Outer_1RB_Right		
9	Default	Delault	Delault	Reduction	DFT-s-OFDM 64 QAM	Outer_Full		
10	Low			(MPR) test	CP-OFDM QPSK	Outer_1RB_Left		
11	High			case	CP-OFDM QPSK	Outer_1RB_Right		
12	Default				CP-OFDM QPSK	Outer_Full		
13	Low				CP-OFDM 16 QAM	Outer_1RB_Left		
14	High				CP-OFDM 16 QAM	Outer_1RB_Right		
15	Default				CP-OFDM 16 QAM	Outer_Full		
16	Low				CP-OFDM 64 QAM	Outer_1RB_Left		
17	High				CP-OFDM 64 QAM	Outer_1RB_Right		
18	Default				CP-OFDM 64 QAM	Outer_Full		
NOTE	1: The s	specific co	nfiguration	n of each RF alloc	ation is defined in Table 6	.1-1.		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2.2.4.1-1 to Table 6.2.2.4.1-9.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2.2.4.3.

#### 6.2.2.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.2.2.4.1-1 to Table 6.2.2.4.1-9. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200ms for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.

- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in 6.2.2.5. EIRP test procedure is defined in Annex K.1.3. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 2: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.2.2.4.1-1 to Table 6.2.2.4.1-9, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.2.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

### 6.2.2.5 Test requirement

The maximum output power, derived in step 5 shall be within the range prescribed by the nominal maximum output power and tolerance in following tables.

Test Configuration Table	Test ID	PPowerclass	MPR <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
	1	40	14.4	7	18.6-TT	55
	2	40	14.4	7	18.6-TT	55
Table 6.2.2.4.1-1	3	40	10	5	25-TT	55
Table 6.2.2.4.1-1	4	40	10	5	25-TT	55
	5	40	10	5	25-TT	55
	6	40	10	5	25-TT	55
	1	40	5.5	5	29.5-TT	55
	2	40	5.5	5	29.5-TT	55
	3	40	5.5	5	29.5-TT	55
	4	40	3	2	35-TT	55
	5	40	4	3	33-TT	55
	6	40	6.5	5	28.5-TT	55
	7	40	6.5	5	28.5-TT	55
	8	40	6.5	5	28.5-TT	55
Table 6.2.2.4.1-2	9	40	5	4	31-TT	55
	10	40	4.5	4	31.5-TT	55
	11	40	7	5	28-TT	55
	12	40	7	5	28-TT	55
	13	40	7	5	28-TT	55
	14	40	5.5	5	29.5-TT	55
	15	40	7.5	5	27.5-TT	55
	16	40	7.5	5	27.5-TT	55
	17	40	7.5	5	27.5-TT	55
	1	40	5.5	5	29.5-TT	55
	2	40	5.5	5	29.5-TT	55
	3	40	5.5	5	29.5-TT	55
	4	40	3	2	35-TT	55
	5	40	3.5	3	33.5-TT	55
	6	40	4.5	4	31.5-TT	55
	7	40	6.5	5	28.5-TT	55
	8	40	6.5	5	28.5-TT	55
Table 6.2.2.4.1-3	9	40	6.5	5	28.5-TT	55
	10	40	5	4	31-TT	55
	11	40	7	5	28-TT	55
	12	40	7	5	28-TT	55
	13	40	7	5	28-TT	55
	14	40	6.5	5	28.5-TT	55
	15	40	9	5	26-TT	55
	16	40	9	5	26-TT	55
	17	40	9	5	26-TT	55

Test Configuration Table	Test ID	PPowerclass	MPR <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
	1	38	14.4	7	16.6-TT	55
	2	38	14.4	7	16.6-TT	55
	3	38	10	5	23-TT	55
Table 6.2.2.4.1-1	4	38	10	5	23-TT	55
	5	38	10	5	23-TT	55
	6	38	10	5	23-TT	55
	1	38	5.5	5	27.5-TT	55
	2	38	5.5	5	27.5-TT	55
	3	38	5.5	5	27.5-TT	55
	4	38	3	2	33-TT	55
	5	38	4	3	31-TT	55
	6	38	6.5	5	26.5-TT	55
	7	38	6.5	5	26.5-TT	55
	8	38	6.5	5	26.5-TT	55
Table 6.2.2.4.1-2	9	38	5	4	29-TT	55
	10	38	4.5	4	29.5-TT	55
	11	38	7	5	26-TT	55
	12	38	7	5	26-TT	55
	13	38	7	5	26-TT	55
	14	38	5.5	5	27.5-TT	55
	15	38	7.5	5	25.5-TT	55
	16	38	7.5	5	25.5-TT	55
	17	38	7.5	5	25.5-TT	55
	1	38	5.5	5	27.5-TT	55
	2	38	5.5	5	27.5-TT	55
	3	38	5.5	5	27.5-TT	55
	4	38	3	2	33-TT	55
	5	38	3.5	3	31.5-TT	55
	6	38	4.5	4	29.5-TT	55
	7	38	6.5	5	26.5-TT	55
	8	38	6.5	5	26.5-TT	55
Table 6.2.2.4.1-3	9	38	6.5	5	26.5-TT	55
	10	38	5	4	29-TT	55
	11	38	7	5	26-TT	55
	12	38	7	5	26-TT	55
	13	38	7	5	26-TT	55
	14	38	6.5	5	26.5-TT	55
	15	38	9	5	24-TT	55
	16	38	9	5	24-TT	55
	17	38	9	5	24-TT	55

Table 6.2.2.5-1a: UE Power Class test requirements for Power Class 1 ( for Bands n260 )

Test Configuration Table	Test ID	PPowerclass	<b>MP</b> R <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
Table 6.2.2.4.1-7	1	29	2.5	2	24.5-TT	43
Table 0.2.2.4.1-7	2	29	2.5	2	24.5-TT	43
	1	29	2	1.5	25.5-TT	43
	2	29	3	2	24-TT	43
	3	29	3.5	3	22.5-TT	43
	4	29	3.5	3	22.5-TT	43
	5	29	3.5	3	22.5-TT	43
	6	29	5	4	20-TT	43
	7	29	5.5	5	18.5-TT	43
	8	29	5.5	5	18.5-TT	43
	9	29	5.5	5	18.5-TT	43
Table 6.2.2.4.1-8	10	29	3.5	3	22.5-TT	43
	11	29	4	3	22-TT	43
	12	29	4	3	22-TT	43
	13	29	4	3	22-TT	43
	14	29	5	4	20-TT	43
	15	29	5	4	20-TT	43
	16	29	5	4	20-TT	43
	17	29	7	5	17-TT	43
	18	29	7	5	17-TT	43
	19	29	7	5	17-TT	43
	1	29	3	2	24-TT	43
	2	29	3	2	24-TT	43
	3	29	3	2	24-TT	43
	4	29	4.5	4	20.5-TT	43
	5	29	4.5	4	20.5-TT	43
	6	29	4.5	4	20.5-TT	43
	7	29	6.5	5	17.5-TT	43
	8	29	6.5	5	17.5-TT	43
Table 6.2.2.4.1.0	9	29	6.5	5	17.5-TT	43
Table 6.2.2.4.1-9	10	29	5	4	20-TT	43
	11	29	5	4	20-TT	43
	12	29	5	4	20-TT	43
	13	29	6.5	5	17.5-TT	43
	14	29	6.5	5	17.5-TT	43
	15	29	6.5	5	17.5-TT	43
	16	29	9	5	15-TT	43
	17	29	9	5	15-TT	43
	18	29	9	5	15-TT	43

Table 6.2.2.5-2: UE Power Class test requirements for Power Class 2

Test Configuration Table	Test ID	PPowerclass	MPR <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
Table	1	22.4	2.5	2	17.9-TT-∆MB <sub>P,n</sub>	43
6.2.2.4.1-7	2	22.4	2.5	2	17.9-TT-ΔMB <sub>P,n</sub>	43
	1	22.4	2	1.5	18.9-TT-ΔMB <sub>P,n</sub>	43
	2	22.4	3	2	17.4-TT-ΔMB <sub>P,n</sub>	43
	3	22.4	3.5	3	15.9-TT-ΔMB <sub>P,n</sub>	43
	4	22.4	3.5	3	15.9-TT-ΔMB <sub>P,n</sub>	43
	5	22.4	3.5	3	15.9-TT-ΔMB <sub>P,n</sub>	43
	6	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	7	22.4	5.5	5	11.9-TT-ΔMB <sub>P,n</sub>	43
	8	22.4	5.5	5	11.9-TT-ΔMB <sub>P,n</sub>	43
	9	22.4	5.5	5	11.9-TT-ΔMB <sub>P,n</sub>	43
Table 6.2.2.4.1-8	10	22.4	3.5	3	15.9-TT-ΔMB <sub>P,n</sub>	43
0.2.2.4.1-0	11	22.4	4	3	15.4-TT-ΔMB <sub>P,n</sub>	43
	12	22.4	4	3	15.4-TT-ΔMB <sub>P,n</sub>	43
	13	22.4	4	3	15.4-TT-ΔMB <sub>P,n</sub>	43
-	14	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	15	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	16	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	17	22.4	7	5	10.4-TT-ΔMB <sub>P,n</sub>	43
	18	22.4	7	5	10.4-TT-ΔMB <sub>P,n</sub>	43
	19	22.4	7	5	10.4-TT-ΔMB <sub>P,n</sub>	43
	1	22.4	3	2	17.4-TT-ΔMB <sub>P,n</sub>	43
	2	22.4	3	2	17.4-TT-ΔMB <sub>P,n</sub>	43
	3	22.4	3	2	17.4-TT-ΔMB <sub>P,n</sub>	43
	4	22.4	4.5	4	13.9-TT-ΔMB <sub>P,n</sub>	43
	5	22.4	4.5	4	13.9-TT-ΔMB <sub>P.n</sub>	43
	6	22.4	4.5	4	13.9-TT-ΔMB <sub>P,n</sub>	43
	7	22.4	6.5	5	10.9-TT-ΔMB <sub>P,n</sub>	43
	8	22.4	6.5	5	10.9-TT-ΔMB <sub>P,n</sub>	43
Table	9	22.4	6.5	5	10.9-TT-ΔMB <sub>P.n</sub>	43
6.2.2.4.1-9	10	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	11	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	12	22.4	5	4	13.4-TT-ΔMB <sub>P,n</sub>	43
	13	22.4	6.5	5	10.9-TT-ΔMB <sub>P,n</sub>	43
	14	22.4	6.5	5	10.9-TT-ΔMB <sub>P,n</sub>	43
	15	22.4	6.5	5	10.9-TT-ΔMB <sub>P,n</sub>	43
	16	22.4	9	5	8.4-TT-ΔMB <sub>P,n</sub>	43
	17	22.4	9	5	8.4-TT-ΔMB <sub>P,n</sub>	43
	18	22.4	9	5	8.4-TT-ΔMB <sub>P,n</sub>	43
TS38	.508-2. Th supporte	ultiband Relaxa is declaration sl	hall fulfil the r	equirements in	E for the tested band in t clause 6.2.1.1.3.3. ultiband relaxation decla	

## Table 6.2.2.5-3: UE Power Class test requirements for Power Class 3 (n257, 258, 261)

1         2         1         2         3         4         5         6         7         8         9         10         11         12         13         14         15         16         17	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	2.5 2.5 2 3 3.5 3.5 3.5 5.5 5.5 5.5 5.5 5.5 5.5 3.5 4 4 4 4 5 5 5	2 2 1.5 2 3 3 3 3 4 5 5 5 5 5 3 3 3 3 3 3 3 3	16.1-TT-ΔMB <sub>P,n</sub> 16.1-TT-ΔMB <sub>P,n</sub> 17.1-TT-ΔMB <sub>P,n</sub> 15.6-TT-ΔMB <sub>P,n</sub> 14.1-TT-ΔMB <sub>P,n</sub> 14.1-TT-ΔMB <sub>P,n</sub> 11.6-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43 43 43 43 43 43 43 43 43 43 43 4
1         2         3         4         5         6         7         8         9         10         11         12         13         14         15         16	20.6         20.6	2 3 3.5 3.5 5 5.5 5.5 5.5 3.5 4 4 4 4 5	1.5 2 3 3 3 4 5 5 5 5 3 3 3 3 3	17.1-TT-ΔMBP,n         15.6-TT-ΔMBP,n         14.1-TT-ΔMBP,n         14.1-TT-ΔMBP,n         14.1-TT-ΔMBP,n         11.6-TT-ΔMBP,n         10.1-TT-ΔMBP,n         10.1-TT-ΔMBP,n         10.1-TT-ΔMBP,n         13.6-TT-ΔMBP,n         13.6-TT-ΔMBP,n         13.6-TT-ΔMBP,n         13.6-TT-ΔMBP,n	43 43 43 43 43 43 43 43 43 43 43 43 43 4
2 3 4 5 6 7 8 9 10 11 12 13 14 15 16	20.6         20.6	3 3.5 3.5 5 5.5 5.5 5.5 3.5 4 4 4 4 5	2 3 3 3 4 5 5 5 5 3 3 3 3 3	15.6-TT-ΔMBP,n           14.1-TT-ΔMBP,n           14.1-TT-ΔMBP,n           14.1-TT-ΔMBP,n           11.6-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n	43 43 43 43 43 43 43 43 43 43 43 43 43
3         4         5         6         7         8         9         10         11         12         13         14         15         16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	3.5 3.5 5 5.5 5.5 5.5 3.5 4 4 4 4 5	3 3 3 4 5 5 5 5 3 3 3 3 3	14.1-TT-ΔMBP,n           14.1-TT-ΔMBP,n           14.1-TT-ΔMBP,n           11.6-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n	43 43 43 43 43 43 43 43 43 43 43 43
4         5         6         7         8         9         10         11         12         13         14         15         16	20.6         20.6	3.5 3.5 5 5.5 5.5 3.5 4 4 4 4 5	3 3 4 5 5 5 3 3 3 3 3	14.1-TT-ΔMBP,n           14.1-TT-ΔMBP,n           11.6-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n	43 43 43 43 43 43 43 43 43 43 43
5         6         7         8         9         10         11         12         13         14         15         16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	3.5 5 5.5 5.5 5.5 3.5 4 4 4 4 5	3 4 5 5 5 3 3 3 3	14.1-TT-ΔMBP,n           11.6-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           10.1-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n           13.6-TT-ΔMBP,n	43 43 43 43 43 43 43 43 43 43
6         7         8         9         10         11         12         13         14         15         16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	5 5.5 5.5 3.5 4 4 4 4 5	4 5 5 3 3 3 3	11.6-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43 43 43 43 43 43
7       8       9       10       11       12       13       14       15       16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	5.5 5.5 3.5 4 4 4 4 5	5 5 3 3 3 3	10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 14.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43 43 43 43 43
8 9 10 11 12 13 14 15 16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	5.5 5.5 3.5 4 4 4 4 5	5 5 3 3 3 3	10.1-TT-ΔMB <sub>P,n</sub> 10.1-TT-ΔMB <sub>P,n</sub> 14.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43 43 43 43
9       10       11       12       13       14       15       16	20.6 20.6 20.6 20.6 20.6 20.6 20.6 20.6	5.5 3.5 4 4 4 4 5	5 3 3 3	10.1-TT-ΔMB <sub>P,n</sub> 14.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43 43 43
10       11       12       13       14       15       16	20.6 20.6 20.6 20.6 20.6 20.6 20.6	3.5 4 4 4 5	3 3 3	14.1-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43 43
11       12       13       14       15       16	20.6 20.6 20.6 20.6 20.6 20.6	4 4 4 5	3 3	13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43 43
12 13 14 15 16	20.6 20.6 20.6 20.6 20.6	4 4 5	3	13.6-TT-ΔMB <sub>P,n</sub> 13.6-TT-ΔMB <sub>P,n</sub>	43
13 14 15 16	20.6 20.6 20.6	4 5		13.6-TT-ΔМВ <sub>Р,n</sub>	-
14 15 16	20.6 20.6	5	3	· · · · · ·	43
15 16	20.6				10
16		5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
	20.6	5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
17		5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
	20.6	7	5	8.6-TT-ΔMB <sub>P,n</sub>	43
18	20.6	7	5	8.6-TT-ΔMB <sub>P,n</sub>	43
19	20.6	7	5	8.6-TT-ΔMB <sub>P,n</sub>	43
1	20.6	3	2	15.6-TT-ΔMB <sub>P,n</sub>	43
2	20.6	3	2	15.6-TT-ΔMB <sub>P,n</sub>	43
3	20.6	3	2	15.6-TT-ΔMB <sub>P,n</sub>	43
4	20.6	4.5	4	12.1-TT-ΔMB <sub>P,n</sub>	43
5	20.6	4.5	4	12.1-TT-ΔMB <sub>P,n</sub>	43
6	20.6	4.5	4	12.1-TT-ΔMB <sub>P,n</sub>	43
7	20.6	6.5	5	9.1-TT-ΔMB <sub>P,n</sub>	43
8	20.6	6.5	5	9.1-TT-ΔMB <sub>P,n</sub>	43
9	20.6	6.5	5	9.1-TT-∆MB <sub>P,n</sub>	43
10	20.6	5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
11	20.6	5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
12	20.6	5	4	11.6-TT-ΔMB <sub>P,n</sub>	43
13	20.6	6.5	5	9.1-TT-ΔMB <sub>P,n</sub>	43
14	20.6	6.5	5	9.1-TT-ΔMB <sub>P,n</sub>	43
15	20.6	6.5	5	9.1-TT-ΔMB <sub>P,n</sub>	43
16	20.6	9	5	6.6-TT-ΔMB <sub>P,n</sub>	43
17	20.6	9	5	6.6-TT-ΔMB <sub>P,n</sub>	43
18	20.6	9	5	$6.6$ -TT- $\Delta MB_{P,n}$	43
1	2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 s the Mu 8-2. This	2         20.6           3         20.6           4         20.6           5         20.6           6         20.6           7         20.6           8         20.6           9         20.6           10         20.6           11         20.6           12         20.6           13         20.6           14         20.6           15         20.6           16         20.6           17         20.6           18         20.6           Sthe Multiband Relaxa           8-2. This declaration supported bands needs	2         20.6         3           3         20.6         3           4         20.6         4.5           5         20.6         4.5           6         20.6         4.5           7         20.6         6.5           8         20.6         6.5           9         20.6         6.5           10         20.6         5           11         20.6         5           12         20.6         5           13         20.6         6.5           14         20.6         6.5           15         20.6         6.5           16         20.6         9           17         20.6         9           18         20.6         9           18         20.6         9           18         20.6         9           18         20.6         9           19         3         3	2       20.6       3       2         3       20.6       3       2         4       20.6       4.5       4         5       20.6       4.5       4         6       20.6       4.5       4         7       20.6       6.5       5         8       20.6       6.5       5         9       20.6       6.5       5         9       20.6       5       4         11       20.6       5       4         12       20.6       5       4         13       20.6       6.5       5         14       20.6       5       5         15       20.6       6.5       5         14       20.6       6.5       5         15       20.6       9       5         16       20.6       9       5         17       20.6       9       5         18       20.6       9       5         18       20.6       9       5         18       20.6       9       5         19       5       5       6         10	220.63215.6-TT- $\Delta MB_{P,n}$ 320.63215.6-TT- $\Delta MB_{P,n}$ 420.64.5412.1-TT- $\Delta MB_{P,n}$ 520.64.5412.1-TT- $\Delta MB_{P,n}$ 620.64.5412.1-TT- $\Delta MB_{P,n}$ 720.66.559.1-TT- $\Delta MB_{P,n}$ 820.66.559.1-TT- $\Delta MB_{P,n}$ 920.66.559.1-TT- $\Delta MB_{P,n}$ 1020.65411.6-TT- $\Delta MB_{P,n}$ 1120.65411.6-TT- $\Delta MB_{P,n}$ 1220.65411.6-TT- $\Delta MB_{P,n}$ 1320.66.559.1-TT- $\Delta MB_{P,n}$ 1420.66.559.1-TT- $\Delta MB_{P,n}$ 1520.66.559.1-TT- $\Delta MB_{P,n}$ 1620.6956.6-TT- $\Delta MB_{P,n}$ 1720.6956.6-TT- $\Delta MB_{P,n}$

Table 6.2.2.5-3a: UE Power Class test requirements for Power Class 3 (n260)

## Table 6.2.2.5-3b: Test Tolerance (Power class 3)

Test Metric	FR2a	FR2b	
Quiet Zone size ≤ 30 cm	3.11 dB	3.11 dB	

## Table 6.2.2.5-4: UE Power Class test requirements for Power Class 4 (n257, 258, 261)

Test Configuration Table	Test ID	PPowerclass	MPR <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
	1	34	2.5	2	29.5-TT	43
Table 6.2.2.4.1-7	2	34	2.5	2	29.5-TT	43
	1	34	2	1.5	30.5-TT	43
	2	34	3	2	29-TT	43
	3	34	3.5	3	27.5-TT	43
	4	34	3.5	3	27.5-TT	43
	5	34	3.5	3	27.5-TT	43
	6	34	5	4	25-TT	43
	7	34	5.5	5	23.5-TT	43
	8	34	5.5	5	23.5-TT	43
	9	34	5.5	5	23.5-TT	43
Table 6.2.2.4.1-8	10	34	3.5	3	27.5-TT	43
	11	34	4	3	27-TT	43
	12	34	4	3	27-TT	43
	13	34	4	3	27-TT	43
	14	34	5	4	25-TT	43
	15	34	5	4	25-TT	43
	16	34	5	4	25-TT	43
	17	34	7	5	22-TT	43
	18	34	7	5	22-TT	43
	19	34	7	5	22-TT	43
	1	34	3	2	29-TT	43
	2	34	3	2	29-TT	43
	3	34	3	2	29-TT	43
	4	34	4.5	4	25.5-TT	43
	5	34	4.5	4	25.5-TT	43
	6	34	4.5	4	25.5-TT	43
	7	34	6.5	5	22.5-TT	43
	8	34	6.5	5	22.5-TT	43
Table 6 2 2 4 1 0	9	34	6.5	5	22.5-TT	43
Table 6.2.2.4.1-9	10	34	5	4	25-TT	43
	11	34	5	4	25-TT	43
	12	34	5	4	25-TT	43
	13	34	6.5	5	22.5-TT	43
	14	34	6.5	5	22.5-TT	43
	15	34	6.5	5	22.5-TT	43
	16	34	9	5	20-TT	43
	17	34	9	5	20-TT	43
	18	34	9	5	20-TT	43

Test Configuration Table	Test ID	PPowerclass	MPR <sub>f,c</sub>	T(MPR <sub>f,c</sub> )	Lower limit (dBm)	Upper limit (dBm)
	1	31	2.5	2	26.5-TT	43
Table 6.2.2.4.1-7	2	31	2.5	2	26.5-TT	43
	1	31	2	1.5	27.5-TT	43
	2	31	3	2	26-TT	43
	3	31	3.5	3	24.5-TT	43
	4	31	3.5	3	24.5-TT	43
	5	31	3.5	3	24.5-TT	43
	6	31	5	4	22-TT	43
	7	31	5.5	5	20.5-TT	43
	8	31	5.5	5	20.5-TT	43
	9	31	5.5	5	20.5-TT	43
Table 6.2.2.4.1-8	10	31	3.5	3	24.5-TT	43
	11	31	4	3	24-TT	43
	12	31	4	3	24-TT	43
	13	31	4	3	24-TT	43
	14	31	5	4	22-TT	43
	15	31	5	4	22-TT	43
	16	31	5	4	22-TT	43
	17	31	7	5	19-TT	43
	18	31	7	5	19-TT	43
	19	31	7	5	19-TT	43
	1	31	3	2	26-TT	43
	2	31	3	2	26-TT	43
	3	31	3	2	26-TT	43
	4	31	4.5	4	22.5-TT	43
	5	31	4.5	4	22.5-TT	43
	6	31	4.5	4	22.5-TT	43
	7	31	6.5	5	19.5-TT	43
	8	31	6.5	5	19.5-TT	43
Table 6.2.2.4.1-9	9	31	6.5	5	19.5-TT	43
Table 0.2.2.4.1-9	10	31	5	4	22-TT	43
	11	31	5	4	22-TT	43
	12	31	5	4	22-TT	43
	13	31	6.5	5	19.5-TT	43
	14	31	6.5	5	19.5-TT	43
	15	31	6.5	5	19.5-TT	43
	16	31	9	5	17-TT	43
	17	31	9	5	17-TT	43
	18	31	9	5	17-TT	43

Table 6.2.2.5-4a: UE Power Class test requirements for Power Class 4 (n260)

## 6.2.3 UE maximum output power with additional requirements

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are FFS.
- Multiband relaxation is not considered in test requirements
- Measurment with modifiedMPRbehavior is FFS.
- Test description and Test requirements subsections for NS 202 and NS 203 are incomplete

#### 6.2.3.1 Test purpose

Additional spectrum emission requirements can be signalled by the network to indicate that the UE shall also meet additional requirements in a specific deployment scenario. To meet these additional requirements, Additional Maximum Power Reduction A-MPR is allowed for the output power.

#### 6.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

- 6.2.3.3 Minimum conformance requirements
- 6.2.3.3.1 General

Additional emission requirements can be signalled by the network. Each additional emission requirement is associated with a unique network signalling (NS) value indicated in RRC signalling by an NR frequency band number of the applicable operating band and an associated value in the field *additionalSpectrumEmission*. Throughout this specification, the notion of indication or signalling of an NS value refers to the corresponding indication of an NR frequency band number of the applicable operating band (the IE field *freqBandIndicatorNR*) and an associated value of additionalSpectrumEmission in the relevant RRC information elements

To meet these additional requirements, additional maximum power reduction (A-MPR) is allowed for the maximum output power as specified in subclause 6.2.1.1.3. Unless stated otherwise, an A-MPR of 0 dB shall be used.

Table 6.2.3.3.1-1 specifies the additional requirements with their associated network signalling values and the allowed A-MPR and applicable operating band(s) for each NS value. The mapping of NR frequency band numbers and values of and the *additionalSpectrumEmission* to network signalling labels is specified in Table 6.2.3.3.1-2. Unless otherwise stated, the allowed total back off is maximum of A-MPR and MPR specified in subclause 6.2.2.

Network Signalling Iabel	Requirements (subclause)	NR Band	Channel bandwidth (MHz)	Resources Blocks ( <i>N</i> <sub>RB</sub> )	A-MPR (dB)	
NS_200					N/A	
NS_201	6.5.3.3.3	n258			6.2.3.2	
NS_202	6.5.3.2.3	n257, n258			6.2.3.3.3	
NS_203	6.5.3.2.4	n258			6.2.3.3.4	
NOTE: NS_201 is obsolete, the associated additional spurious emission requirements are not applicable.						

Table 6.2.3.3.1-1: Additional maximum power reduction (A-MPR)

NR Band		Value of additionalSpectrumEmission							
	0	1	2	3	4	5	6	7	
n257	NS_200	NS_202	NS_202	NS_203					
n258	NS_200	NS_201 <sup>2</sup>							
n260	NS_200								
n261 NS_200									
NOTE: additionalSpectrumEmission corresponds to an information element of the same name defined in									
sub-clause 6.3.2 of TS 38.331 [19].									
NOTE 2: NS	_201 is obs	olete, the as	sociated add	itional spuric	ous emission	requirement	ts are not ap	plicable.	

Table 6.2.3.3.1-2: Mapping of Network Signalling label

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.3.1.

6.2.3.3.2 Void

6.2.3.3.2.1 Void

For power class 1, A-MPR for NS\_201 shall be 9 dB.

#### Table 6.2.3.3.2.1-1: Void

- 6.2.3.3.2.2 Void
- 6.2.3.3.2.3 Void
- 6.2.3.3.3 A-MPR for NS\_202
- 6.2.3.3.3.1 A-MPR for NS\_202 for power class 1

For power class 1, A-MPR for NS\_202 shall be 11.0 dB.

6.2.3.3.3.2 A-MPR for NS\_202 for power class 2

For power class 2, A-MPR for NS\_202 specified in clause 6.2.3.3.3 applies.

6.2.3.3.3.3 A-MPR for NS\_202 for power class 3

For power class 3, A-MPR for NS\_202 shall be 1.0 dB.

6.2.3.3.3.4 A-MPR for NS\_202 for power class 4

For power class 4, A-MPR for NS\_202 specified in clause 6.2.3.3.3 applies.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.3.3.

#### 6.2.3.3.4 A-MPR for NS\_203

6.2.3.3.4.1 A-MPR for NS\_203 for power class 1

For power class 1, A-MPR for NS\_203 shall be 3.0 dB if Offset frequency  $< BW_{channel}$ , 0.0 dB otherwise. The Offset frequency is defined as the frequency from 24.25 GHz to the lower edge of the channel bandwidth.

#### 6.2.3.3.4.2 A-MPR for NS\_203 for power class 2

For power class 2, A-MPR for NS\_203 specified in clause 6.2.3.3.4.3 applies.

#### 6.2.3.3.4.3 A-MPR for NS\_203 for power class 3

For power class 3, A-MPR for NS\_203 shall be 0 dB.

6.2.3.3.4.4 A-MPR for NS\_203 for power class 4

For power class 4, A-MPR for NS\_203 specified in clause 6.2.3.3.4.3 applies.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2.3.4.

6.2.3.4 Test description

#### 6.2.3.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

#### Table 6.2.3.4.1-1: Void

#### Table 6.2.3.4.1-2: Test configuration table for NS\_202

#### [TBD]

#### Table 6.2.3.4.1-3: Test configuration table for NS\_203

#### [TBD]

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.1.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The DL and UL Reference Measurement channels are set according to Table 6.2.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2.3.4.3

#### 6.2.3.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.2.1.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2.1.1.4.3.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec starting from the first TPC command in this step to ensure that the UE transmits at its

maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.

- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.1.5-1. EIRP test procedure is defined in Annex K. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6, with the following exceptions for each network signalled value.

1. Information element AdditionalSpectrumEmission for NR can be set in SIB1 according to TS 38.331[19]. This exception indicates that the UE shall meet the additional spurious emission requirement for a specific deployment scenario.

#### Table 6.2.3.4.3-1: AdditionalSpectrumEmission: Additional spurious emissions test requirement

Derivation Path: TS 38.508-1 [10] clause 4.6.3, Table 4.6.3-1						
Information Element	Value/remark	Comment	Condition			
AdditionalSpectrumEmission	2 (NS_202)	for band n257, n258				
AdditionalSpectrumEmission	3 (NS_203)	for band n258				

#### 6.2.3.5 Test requirement

The UE EIRP derived in step 5 shall not exceed the values specified in Table 6.2.3.5-1.

Table 6.2.3.5-1: Void

Table 6.2.3.5-2: Void

Table 6.2.3.5-3: Void

#### Table 6.2.3.5-4: UE Power Class 4 test requirements (network signalled value "NS\_201")

[TBD]

Table 6.2.3.5-5: UE Power Class 1 test requirements (network signalled value "NS\_202")

[TBD]

Table 6.2.3.5-6: UE Power Class 2 test requirements (network signalled value "NS\_202")

[TBD]

Table 6.2.3.5-7: UE Power Class 3 test requirements (network signalled value "NS\_202")

[TBD]

Table 6.2.3.5-8: UE Power Class 4 test requirements (network signalled value "NS\_202")

[TBD]

Table 6.2.3.5-9: UE Power Class 4 test requirements (network signalled value "NS\_203")

[TBD]

Table 6.2.3.5-10: UE Power Class 4 test requirements (network signalled value "NS\_203")

[TBD]

Table 6.2.3.5-11: UE Power Class 4 test requirements (network signalled value "NS\_203")

#### [TBD]

#### Table 6.2.3.5-12: UE Power Class 4 test requirements (network signalled value "NS\_203")

[TBD]

## 6.2.4 Configured transmitted power

#### 6.2.4.1 Test purpose

To verify the UE transmitted power  $P_{UMAX,f,c}$  is within the range defined prescribed by the specified nominal maximum output power and tolerance.

#### 6.2.4.2 Test applicability

The requirements of this test are covered in test cases 6.2.1 Maximum output power, 6.2.2 Maximum output power reduction and 6.2.3 UE maximum output power with additional requirements to all types of NR UE release 15 and forward.

#### 6.2.4.3 Minimum conformance requirements

The UE can configure its maximum output power. The configured UE maximum output power  $P_{CMAX,f,c}$  for carrier f of a serving cell c is defined as that available to the reference point of a given transmitter branch that corresponds to the reference point of the higher-layer filtered RSRP measurement as specified in TS 38.215 [24].

The configured UE maximum output power  $P_{CMAX,f,c}$  for carrier *f* of a serving cell *c* shall be set such that the corresponding measured peak EIRP  $P_{UMAX,f,c}$  is within the following bounds

$$\begin{split} P_{Powerclass} - MAX(MAX(MPR_{f,c}, \text{A-} MPR_{f,c}) + \Delta MB_{P,n}, P-MPR_{f,c}) - MAX\{T(MAX(MPR_{f,c}, \text{A-} MPR_{f,c})), T(P-MPR_{f,c})\} \\ \leq P_{UMAX,f,c} \leq EIRP_{max} \end{split}$$

while the corresponding measured total radiated power P<sub>TMAX,f,c</sub> is bounded by

$$P_{TMAX,f,c} \leq TRP_{max}$$

with  $P_{Powerclass}$  the UE power class as specified in sub-clause 6.2.1.1.3, EIRP<sub>max</sub> the applicable maximum EIRP as specified in sub-clause 6.2.1.1.3, MPR<sub>f,c</sub> as specified in sub-clause 6.2.2.3, A-MPR<sub>f,c</sub> as specified in sub-clause 6.2.3.3,  $\Delta MB_{P,n}$  the peak EIRP relaxation as specified in section 6.2.1.1.3 and TRP<sub>max</sub> the maximum TRP for the UE power class as specified in sub-clause 6.2.1.1.3.

*maxUplinkDutyCycle-FR2* as defined in TS 38.306 [14] is a UEcapability to facilitate electromagnetic power density exposure requirements. This UE capability is applicable to all FR2 power classes.

If the field of UE capability *maxUplinkDutyCycle-FR2* is present and the percentage of uplink symbols transmitted within any 1 s evaluation period is larger than maxUplinkDutyCycle-FR2, the UE follows the uplink scheduling and can apply P-MPR<sub>f.c</sub>.

If the field of UE capability *maxUplinkDutyCycle-FR2* is absent, the compliance to electromagnetic power density exposure requirements are ensured by means of scaling down the power density or by other means.

 $P-MPR_{f,c}$  is the allowed maximum output power reduction. The UE shall apply  $P-MPR_{f,c}$  for carrier f of serving cell c only for the cases described below. For UE conformance testing  $P-MPR_{f,c}$  shall be 0 dB.

- a) ensuring compliance with applicable electromagnetic power density exposure requirements and addressing unwanted emissions / self-defence requirements in case of simultaneous transmissions on multiple RAT(s) for scenarios not in scope of 3GPP RAN specifications;
- b) ensuring compliance with applicable electromagnetic power density exposure requirements in case of proximity detection is used to address such requirements that require a lower maximum output power.
- NOTE 1: P-MPR<sub>f,c</sub> was introduced in the P<sub>CMAX,f,c</sub> equation such that the UE can report to the gNB the available maximum output transmit power. This information can be used by the gNB for scheduling decisions.
- NOTE 2: P-MPR<sub>f,c</sub> and *maxUplinkDutyCycle-FR2* may impact the maximum uplink performance for the selected UL transmission path.

The tolerance  $T(\Delta P)$  for applicable values of  $\Delta P$  (values in dB) is specified in Table 6.2.4.3-1.

Operating Band	∆ <b>P (dB)</b>	Tolerance T(∆P) (dB)		
	$\Delta P = 0$	0		
	0 < ∆P ≤ 2	[1.5]		
	2 < ∆P ≤ 3	[2.0]		
n257, n258, n260,	3 < ∆P ≤ 4	[3.0]		
n261	4 < ∆P ≤ 5	[4.0]		
	5 < ∆P ≤ 10	[5.0]		
	10 < ∆P ≤ 15	[7.0]		
	15 < ∆P ≤ X	[8.0]		
NOTE: X is the value such that Pumax, f,c lower bound, PPowerclass -				
$\Delta P - T(\Delta P) = minimum output power specified in$				
subclause 6	5.3.1			

Table 6.2.4.3-1: PUMAX, f, c tolerance

### 6.2.4.4 Test description

This test is covered by clause 6.2.1 Maximum output power, 6.2.2 Maximum output power reduction and 6.2.3 UE maximum output power with additional requirements.

#### 6.2.4.5 Test requirements

This test is covered by clause 6.2.1 Maximum output power, 6.2.2 Maximum output power reduction and 6.2.3 UE maximum output power with additional requirements.

## 6.2A Transmit power for CA

## 6.2A.1 UE maximum output power for CA

### 6.2A.1.0 Minimum conformance requirements

For downlink intra-band contiguous and non-contiguous carrier aggregation with a single uplink component carrier configured in the NR band, the maximum output power is specified in subclause 6.2.1.1.3.

For uplink intra-band contiguous carrier aggregation for any CA bandwidth class, the maximum output power is specified in subclause 6.2.1.1.3.

Power class 3 is default power class.

## 6.2A.1.1 UE maximum output power - EIRP and TRP for CA

### 6.2A.1.1.1 UE maximum output power - EIRP and TRP for CA (2UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Procedures for EIRP beam peak Extreme Conditions are FFS.

#### 6.2A.1.1.1.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth for CA under the deployment scenarios where additional requirements are specified.

6.2A.1.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

	6.2A.1.1.1.3	Minimum	conformance	requirements
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The minimum conformance requirements are defined in clause6.2A.1.0.

6.2A.1.1.1.4 Test description

6.2A.1.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2A.1.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

		D	efault Conditions				
Test Envi	ronment as specified in TS	\$ 38.508-1 [10] subc	clause [4.1]	Normal, TL/VL, TL/VH, TH/VL, TH/VH (NOTE 2)			
different C	uencies as specified in TS CA bandwidth classes	Low and High range					
specified in Table 5.5A.1-1 for the CA Configuration across bandwidth				configuration	Highest aggregated BW of the CA configuration (≤ 400 MHz aggregated channel bandwidth)		
	as specified in Table 5.3.			120 kHz	, , , , , , , , , , , , , , , , , , , ,		
	·		Test Parameters	·			
C	A Configuration / Aggre	gated BW	Downlink Configuration	Uplink Cor	nfiguration		
Test ID	CC & Mapping (NOTE 4)	CBW (MHz)	RB allocation	Modulation	RB allocation (NOTE 1)		
1	PCC/CC1	100	N/A for this test	DFT-s-OFDM QPSK	Inner Full for PC2, PC3 and PC4 Inner_Full_Region1 for PC1		
	SCC/CC2	100	1	-	-		
2	PCC/CC1	200		DFT-s-OFDM QPSK	Inner Full for PC2, PC3 and PC4 Inner_Full_Region1 for PC1		
	SCC/CC2	200		-	-		
NOTE 1:	1: The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						
NOTE 3:	applicable aggregated ch PCC/CCi and SCC/CCj r	Imulative aggregate nannel bandwidths a neans PCC is on co	d BW settings are chec are specified in Table 5.8	ked separately for each CA 5A.1-1. d SCC is on component ca	-		
	CCj frequencies defined						

## Table 6.2A.1.1.1.4.1-1: Intra-band Contiguous CA Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2A.1.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.1.1.1.4.3

#### 6.2A.1.1.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] subclause 5.5.1. Message contents are defined in clause 6.2A.1.1.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [x], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.2A.1.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2A.1.1.1.4.3.

- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec starting from the first TPC command in this step to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 8. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.2A.1.1.1.5-1. EIRP test procedure is defined in Annex K.1.3. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 9. Measure TRP of the transmitted signal for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.2A.1.1.1.5-1. Total radiated power is measured according to TRP measurement procedure defined in Annex K.1.7 and measurement grid specified in Annex M.4. TRP is calculated considering both polarizations, theta and phi.
- 10. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2A.1.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.1.1.5 Test Requirements

The EIRP derived in step 8 and TRP derived in step 9 shall not exceed the values specified in Table 6.2A.1.1.1.5-1 to Table 6.2A.1.1.1.5-4.

Table 6.2A.1.1.1.5-1: Intra-band Contiguous CA UE maximum output test requirements for power class 1
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UL CA configuration	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
CA_n257D	35+TT	55	40-TT
CA_n257G	35+TT	55	40-TT
CA_n260D	35+TT	55	38-TT
CA_n260G	35+TT	55	38-TT
CA_n260O	35+TT	55	38-TT
CA_n261D	35+TT	55	40-TT
CA_n261G	35+TT	55	40-TT
CA_n261O	35+TT	55	40-TT

## Table 6.2A.1.1.1.5-2: Intra-band Contiguous CA UE maximum output test requirements for power class 2

UL CA configuration	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
CA_n257D	23+TT	43	29-TT
CA_n257G	23+TT	43	29-TT
CA_n261D	23+TT	43	29-TT
CA_n261G	23+TT	43	29-TT
CA_n261O	23+TT	43	29-TT

 Table 6.2A.1.1.1.5-3: Intra-band Contiguous CA UE maximum output test requirements for power class 3

UL CA configuration	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
CA_n257D	23+TT	43	22.4-TT
CA_n257G	23+TT	43	22.4-TT
CA_n260D	23+TT	43	20.6-TT
CA_n260G	23+TT	43	20.6-TT
CA_n260O	23+TT	43	20.6-TT
CA_n261D	23+TT	43	22.4-TT
CA_n261G	23+TT	43	22.4-TT
CA_n261O	23+TT	43	22.4-TT

## Table 6.2A.1.1.1.5-3a: UE maximum output test requirements for power class 3 for multi band UE declaring MBp>0 in any FR2 band

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB <sub>P</sub> , ∑MB <sub>P</sub> (dB) (Note 3)	Comments	
		CA_n257D/G	CA_n258	CA_n260D/G/ O	CA_n261D/G/ O		
1	n257, n258	22.4-TT-MBp				1.3	
2	n257, n260	22.4-TT-MBp		20.6-TT-MBp		1.0	
3	n258, n260			20.6-TT-MBp		1.0	
4	n258, n261				22.4-TT-MBp	1.0	
5	n260, n261					0.0	No relaxation factor allowed
6	n257, n258, n260	22.4-TT-MBp		20.6-TT-MBp		1.7	
7	n257, n258, n261	22.4-TT-MBp			22.4-TT-MBp	1.7	
8	n257, n260, n261	22.4-TT-MBp		20.6-TT-MBp	22.4-TT-MBp	0.5	
9	n258, n260, n261			20.6-TT-MBp	22.4-TT-MBp	1.5	
10	n257, n258, n260, n261	22.4-TT-MB <sub>p</sub>		20.6-TT-MB <sub>p</sub>	22.4-TT-MBp	1.7	
Note 1	Note 1: MB <sub>p</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-2 of TS38.508-2. This declaration shall fulfil the requirements in clause 6.2.1.1.3.3.						
Note 2						declaration is co	ompliant
Note 3	B: Max allowed sum of the sum	of MB <sub>p</sub> over all s	upported FR	2 bands as defir	ned in clause 6.2	2.1.1.3.3	

### Table 6.2A.1.1.1.5-3b: Test Tolerance (Max TRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.65 dB	2.77 dB

## Table 6.2A.1.1.1.5-3c: Test Tolerance (Min peak EIRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30cm	2.87 dB	2.87 dB

# Table 6.2A.1.1.1.5-4: Intra-band Contiguous CA UE maximum output test requirements for power class 4

UL CA configuration	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
CA_n257D	23+TT	43	34-TT
CA_n257G	23+TT	43	34-TT
CA_n260B	23+TT	43	31-TT
CA_n260D	23+TT	43	31-TT
CA_n260G	23+TT	43	31-TT
CA_n260O	23+TT	43	31-TT
CA_n261B	23+TT	43	34-TT
CA_n261D	23+TT	43	34-TT
CA_n261G	23+TT	43	34-TT
CA_n261O	23+TT	43	34-TT

## 6.2A.1.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Procedures for EIRP beam peak Extreme Conditions are FFS.

#### 6.2A.1.1.2.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth for CA under the deployment scenarios where additional requirements are specified.

#### 6.2A.1.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.2A.1.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.1.0.

#### 6.2A.1.1.2.4 Test description

Same as in clause 6.2A.1.1.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.1.4.1-1→ use Table 6.2A.1.1.2.4.1-1.
- Instead of clause 6.2A.1.1.1.4.3  $\rightarrow$  use clause 6.2A.1.1.2.4.3.
- Instead of Table 6.2A.1.1.1.5-1  $\rightarrow$  use Table 6.2A.1.1.2.5-1.

### Table 6.2A.1.1.2.4.1-1: Test Configuration Tabl

			Default C	onditions		
	Test Environment as specified in TS 38.508-1 [10] subclause [4.1]			Normal, T	L/VL, TL/VH, TH/VL	_, TH/VH (NOTE 2)
	Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes		Low and H	High range		
Test CC Combination setting (aggregated BW of the CA configuration) as specified in Table 5.5A.1-1 for the CA Configuration across bandwidth combination sets supported by the UE		Highest aggregated BW (≤ 400 MHz aggregated channel bandwidth)				
Test SCS	as specified in Table 5.	3.5-1		120 kHz		
			Test Par	rameters		
CAC				nlink uration	Uplink Configuration	
Test ID	CC & Mapping (NOTE 4)	CBW (MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)
1	PCC/CC1	100	N/A for this test		DFT-s-OFDM QPSK	Inner Full for PC2, PC3 and PC4 Inner_Full_Region1 for PC1
	SCC/CC2	100			-	-
	SCC/CC3	100			-	-

NOTE 1:	The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table
	6.1-2 for PC1.
NOTE 2:	Test environment for UE Max TRP is normal only.
NOTE 3:	CA Configuration Test cumulative aggregated BW settings are checked separately for each CA
	Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.
NOTE 4:	If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated
	BW, only the combination with the lowest PCC ChBW is tested.
NOTE 5:	PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj,
	with CCi or CCj frequencies defined in TS38.508-1 [10].

#### 6.2A.1.1.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.1.2.5 Test Requirements

The EIRP derived in step 8 and TRP derived in step 9 shall not exceed the values specified in Table 6.2A.1.1.2.5-1.

Table 6.2A.1.1.2.5-1: UE maximum ou	tput test requirements for p	power class 3
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CA configuration	Max TRP (dBm)	Max EIRP (dBm)	Min peak EIRP (dBm)
CA_n257H	23+TT	43	22.4-TT

#### Table 6.2A.1.1.2.5-1a: Test Tolerance (Max TRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.65 dB	2.77 dB

#### Table 6.2A.1.1.2.5-1b: Test Tolerance (Min peak EIRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.87 dB	2.87 dB

#### 6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Procedures for EIRP beam peak Extreme Conditions are FFS.

#### 6.2A.1.1.3.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth for CA under the deployment scenarios where additional requirements are specified.

#### 6.2A.1.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.2A.1.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.1.0.

### 6.2A.1.1.3.4 Test description

#### 6.2A.1.1.3.4.1 Initial condition

Same as in clause 6.2A.1.1.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.1.4.1-1→ use Table 6.2A.1.1.3.4.1-1.
- Instead of clause 6.2A.1.1.1.4.3  $\rightarrow$  use clause 6.2A.1.1.3.4.3.
- Instead of Table 6.2A.1.1.1.5-1  $\rightarrow$  use Table 6.2A.1.1.3.5-1.

### Table 6.2A.1.1.3.4.1-1: Test Configuration Table

			Default	Conditions	6	
subclause [4.1]			Normal, TL/VL, TL/VH, TH/VL, TH/VH (NOTE 2)			
Test Freq	uencies as specified in T	S 38.508-1	I [10]	Low and H	ligh range	
subclause	e [4.3.1.2.3] for different (	CA bandwid	dth			
classes, a	and PCC and SCC are m	apped onto	o physical			
frequenci	es according to Table 6.1	-2				
	Combination setting (curr			Highest ag	gregated BW (≤ 400	) MHz aggregated channel
BW of the	CA configuration) as sp	ecified in T	able	bandwidth	)	
5.5A.1-1 f	or the CA Configuration	across ban	dwidth			
	on sets supported by the					
Test SCS	as specified in Table 5.3	3.5-1		120 kHz		
			Test P	arameters		
CA Co	onfiguration / Aggregate	ed BW	Dow	nlink	Uplin	k Configuration
				uration		
Test ID	CC & Mapping (NOTE 4)	ChBw	RB allo	ocation	Modulation	RB allocation (NOTE 1)
	PCC/CC1	100	N/A for	this test	DFT-s-OFDM	Inner Full for PC2, PC3 and
					QPSK	PC4
						Inner_Full_Region1 for
1						PC1
	SCC/CC2	100			-	-
	SCC/CC3	100			-	-
	SCC/CC4	100			-	-
NOTE 1:		on of each	RF allocatio	n is defined	in Table 6.1-1 for P	C2, PC3 and PC4 or Table
	6.1-2 for PC1.					
	Test environment for U					
NOTE 3:	CA Configuration Test of					
	Configuration, which ap					
NOTE 4:						same cumulative aggregated
NOTE -	BW, only the combination					
NOTE 5:					ier CCi and SCC is o	on component carrier CCj,
	with CCi or CCj frequer	cies define	ed in TS38.5	08-1 [10].		

#### 6.2A.1.1.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.1.3.5 Test Requirements

The EIRP derived in step 8 and TRP derived in step 9 shall not exceed the values specified in Table 6.2A.1.1.3.5-1.

## Table 6.2A.1.1.3.5-1: UE maximum output test requirements for power class 3

CA configura	ation Max T	RP (dBm)	Max EIRP (	dBm) Min	peak EIRP (o	dBm)
CA_n257	I 2	3+TT	43		22.4-TT	

#### Table 6.2A.1.1.3.5-1a: Test Tolerance (Max TRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.65 dB	2.77 dB

#### Table 6.2A.1.1.3.5-1b: Test Tolerance (Min peak EIRP for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	2.87 dB	2.87 dB

## 6.2A.1.2 UE maximum output power - Spherical coverage

## 6.2A.1.2.1 Spherical coverage for CA (2UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.

#### 6.2A.1.2.1.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

#### 6.2A.1.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

#### 6.2A.1.2.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

6.2A.1.2.1.4 Test description

#### 6.2A.1.2.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2A.1.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

## Table 6.2A.1.2.1.4.1-1: Intra-band Contiguous CA Test Configuration Table (single CC requirement)

		Default	Conditions		
Test Environment as specified in TS 38.508-1 [10]		Normal (NOTE 2)			
subclause [4.1]					
			Low and H	ligh range	
			Highest aggregated BW (≤ 400 MHz aggregated channel		
, ,			bandwidth	)	
	combination	sets			
	5 2 5 1		120 10-		
as specified in Table :	5.5.5-1	Tost P			
onfiguration / Aggreg	ated BW			Unlin	k Configuration
Singulation / Aggreg				Opini	K configuration
CC & Mapping	CBW			Modulation	RB allocation
	(MHz)				(NOTE 1)
PCC/CC1	100	N/A for	this test	DFT-s-OFDM	Inner Full for PC2, PC3
				QPSK	and PC4
					Inner_Full_Region1 for
					PC1
				-	-
PCC/CC1	200				Inner Full for PC2, PC3
				QPSK	and PC4
					Inner_Full_Region1 for
000/000					PC1
NOTE 1: The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table					
Configuration, which applicable aggregated channel bandwidths are specified in Table 5.54 1-1					
NOTE 3: If the LIE supports multiple CC Combinations in the CA Configuration with the same cumulative accreated					
NOTE 4: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj,					
	e [4.1] uencies as specified in e [4.3.1.2.3] for differen Combination setting (ag tion) as specified in Ta- ation across bandwidth d by the UE is as specified in Table & onfiguration / Aggrega CC & Mapping (NOTE 4) PCC/CC1 SCC/CC2 PCC/CC1 SCC/CC2 PCC/CC1 SCC/CC2 The specific configura- 6.1-2 for PC1. CA Configuration Tes Configuration, which If the UE supports mu BW, only the combina PCC/CCi and SCC/C	a [4.1]         uencies as specified in TS 38.508-1         a [4.3.1.2.3] for different CA bandwic         Combination setting (aggregated BW         tion) as specified in Table 5.5A.1-1 f         ation across bandwidth combination is         d by the UE         c as specified in Table 5.3.5-1         onfiguration / Aggregated BW         CC & Mapping         (NOTE 4)         (MHz)         PCC/CC1         100         SCC/CC2         200         The specific configuration of each         6.1-2 for PC1.         CA Configuration Test cumulative a         Configuration, which applicable ag         If the UE supports multiple CC Cor         BW, only the combination with the         PCC/CCi and SCC/CCj means PC	ronment as specified in TS 38.508-1 [10] e [4.1] juencies as specified in TS 38.508-1 [10] e [4.3.1.2.3] for different CA bandwidth classes Combination setting (aggregated BW of the CA tion) as specified in Table 5.5A.1-1 for the CA ation across bandwidth combination sets d by the UE as specified in Table 5.3.5-1 Test Pa onfiguration / Aggregated BW Config CC & Mapping (NOTE 4) PCC/CC1 100 PCC/CC1 200 SCC/CC2 100 PCC/CC1 200 The specific configuration of each RF allocation 6.1-2 for PC1. CA Configuration Test cumulative aggregated cha If the UE supports multiple CC Combinations in BW, only the combination with the lowest PCC PCC/CC1 and SCC/CCj means PCC is on com	ronment as specified in TS 38.508-1 [10]       Normal (Normal (Normat (Normal (Normal (Normat (Normal (Normal (Normal (Normal (Normal	a [4.1]       Juancies as specified in TS 38.508-1 [10]       Low and High range         a [4.3.1.2.3] for different CA bandwidth classes       Low and High range         Combination setting (aggregated BW of the CA tion) as specified in Table 5.5A.1-1 for the CA tion across bandwidth combination sets       Highest aggregated BW (≤ 400 bandwidth)         a specified in Table 5.5A.1-1 for the CA to bandwidth       Highest aggregated BW (≤ 400 bandwidth)         a specified in Table 5.3.5-1       120 kHz         a specified in Table 5.3.5-1       I20 kHz         c as specified in Table 5.3.5-1       I20 kHz

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals for PCC are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2A.1.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.1.2.1.4.3

#### 6.2A.1.2.1.4.2 Test procedure

- 1. Configure PCC and SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.2A.1.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.2A.1.2.1.4.1-1. Since the UL has no payload and no loopback data

to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2A.1.2.1.4.3.

- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 7. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP measurements for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.3. After a rotation, allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for UE to find the best beam to use. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 8. Calculate a cumulative distribution function for the measured EIRP values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2A.1.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.2.1.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.1.5-1 to Table 6.2A.1.2.1.5-4.

#### Table 6.2A.1.2.1.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
CA_n257D	32.0-TT
CA_n257G	32.0-TT
CA_n260D	30.0-TT
CA_n260G	30.0-TT
CA_n260O	30.0-TT
CA_n261D	32.0-TT
CA_n261G	32.0-TT
CA_n261O	32.0-TT

#### Table 6.2A.1.2.1.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)
CA_n257D	18.0-TT
CA_n257G	18.0-TT
CA_n261D	18.0-TT
CA_n261G	18.0-TT
CA_n261O	18.0-TT

-

Table 6.2A.1.2.1.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single	
band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands	

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)
CA_n257D	11.5-TT
CA_n257G	11.5-TT
CA_n260D	8-TT
CA_n260G	8-TT
CA_n260O	8-TT
CA_n261D	11.5-TT
CA_n261G	11.5-TT
CA_n261O	11.5-TT

Table 6.2A.1.2.1.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB <sub>s</sub> >0 in
any FR2 band

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257D/G	CA_n258	CA_n260D/ G/O	CA_n261D/G/ O		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MBs		8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MBs	1.25	
5	n260, n261			8-TT-MBs	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MBs			11.5-TT-MBs	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MB <sub>s</sub>	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MBs	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 1 Note 2 Note 3	declaration shall ful : All UE supported b	Ifil the requireme ands needs to be	nts in clause e tested to en	6.2.1.1.3.3. sure the multib	and relaxation d	leclaration is c	3 of TS38.508-2. This ompliant

Operating band	Min EIRP at 20%-tile CDF (dBm)
CA_n257D	25-TT
CA_n257G	25-TT
CA_n260D	19-TT
CA_n260G	19-TT
CA_n260O	19-TT
CA_n261D	25-TT
CA_n261G	25-TT
CA_n261O	25-TT

Table 6.2A.1.2.1.5-5: Test Tol	lerance (Spherical coverage)	) (Aggregated BW ≤ 400MHz)
--------------------------------	------------------------------	----------------------------

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	2.58 dB	2.58 dB

## 6.2A.1.2.2 Spherical coverage for CA (3UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2A.1.2.2.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

#### 6.2A.1.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.2A.1.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

6.2A.1.2.2.4 Test description

#### 6.2A.1.2.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2A.1.2.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 6.2A.1.2.2.4.1-1: Intra-band Contiguous CA Test Configuration Table (single CC requirement)

Default Conditions							
Test Environment as specified in TS 38.508-1 [10] subclause				Normal (NOTE 2)			
[4.1]							
	uencies as specified in TS 3		lbclause	Low and High range			
[4.3.1.2.3] for different CA bandwidth classes							
	Combination setting (aggreg				gregated BW (≤ 400 M	Hz aggregated	
	ion) as specified in Table 5.			channel ba	ndwidth)		
	tion across bandwidth comb	ination sets sup	oported by				
the UE	as apparified in Table 5.2.5	4		120 kHz			
1651 303	as specified in Table 5.3.5-		st Paramete				
CA	Configuration / Aggregat		1	nlink	Uplink Conf	iguration	
U.	CA Configuration / Aggregated DW			Configuration		igulation	
Test ID	CC & Mapping (NOTE 4)	CBW (MHz)		ocation	Modulation	RB allocation (NOTE 1)	
1	PCC/CC1	100	N/A for	this test	DFT-s-OFDM QPSK	Inner Full	
I	SCC/CC2	100			-	-	
	SCC/CC3	100			-	-	
NOTE 1:	The specific configuration	of each RF alloc	cation is define	ned in Table	6.1-1 for PC2, PC3 and	d PC4 or Table	
	6.1-2 for PC1.						
NOTE 2:	<b>J</b>						
	Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1. NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated						
NOTE 3:					on with the same cumu	lative aggregated	
NOTE 4:	BW, only the combination v PCC/CCi and SCC/CCj me with CCi or CCj frequencie	eans PCC is on	component	carrier CCi a	nd SCC is on compone	ent carrier CCj,	

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals for PCC are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2A.1.2.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.1.2.2.4.3

#### 6.2A.1.2.2.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.2A.1.2.2.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321[x], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.2A.1.2.2.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2A.1.2.2.4.3.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 7. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP measurements for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.3. After a rotation, allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for UE to find the best beam to use. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 8. Calculate a cumulative distribution function for the measured EIRP values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2A.1.2.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.2.2.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.2.5-1 to Table 6.2A.1.2.2.5-4.

## Table 6.2A.1.2.2.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
CA_n257H	32.0-TT
CA_n260H	30.0-TT
CA_n260P	30.0-TT
CA_n261H	32.0-TT
CA_n261P	32.0-TT

### Table 6.2A.1.2.2.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)			
CA_n257H	18.0-TT			
CA_n261H	18.0-TT			
CA_n261P	18.0-TT			

# Table 6.2A.1.2.2.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)
CA_n257H	11.5-TT
CA_n260H	8-TT
CA_n260P	8-TT
CA_n261H	11.5-TT
CA_n261P	11.5-TT

## Table 6.2A.1.2.2.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB<sub>s</sub>>0 in any FR2 band

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257H	CA_n258	CA_n260H/ P	CA_n261H/P		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MBs	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MB <sub>s</sub>		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB <sub>s</sub>			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MB <sub>s</sub>		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MB <sub>s</sub>	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MB <sub>s</sub>	11.5-TT-MB₅	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 7	Note 1: MB <sub>s</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-3 of TS38.508-2. This declaration shall fulfil the requirements in clause 6.2.1.1.3.3.						
Note 2					and relaxation c	leclaration is co	ompliant
Note 3	Note 3: Max allowed sum of MBs over all supported FR2 bands as defined in clause 6.2.1.1.3.3						

#### Table 6.2A.1.2.2.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)
CA_n257H	25-TT
CA_n260H	19-TT
CA_n260P	19-TT
CA_n261H	25-TT
CA_n261P	25-TT

#### Table 6.2A.1.2.2.5-5: Test Tolerance (Spherical coverage) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b	
IFF (Quiet Zone size ≤ 30 cm)	2.58 dB	2.58 dB	

### 6.2A.1.2.3 Spherical coverage for CA (4UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2A.1.2.3.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

#### 6.2A.1.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.2A.1.2.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

6.2A.1.2.3.4 Test description

#### 6.2A.1.2.3.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.2A.1.2.3.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

## Table 6.2A.1.2.3.4.1-1: Intra-band Contiguous CA Test Configuration Table (single CC requirement)

Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]				Normal		
Test Frequencies as specified in TS 38.508-1 [10]			Low and H	igh range		
	e [4.3.1.2.3] for different CA					
	and SCC are mapped onto	physical fr	equencies			
	to Table 6.1-2					
	Combination setting (cumula				gregated BW (≤ 400 MHz a	aggregated
	configuration) as specified			channel ba	indwidth)	
	onfiguration across bandwid	th combination	ation sets			
	by the UE	4		400.111		
Test SCS	as specified in Table 5.3.5	-1	Taat Daw	120 kHz		
	enfiguration / Agence ato		Test Para		Unlink Confid	unation.
	onfiguration / Aggregate	ави		vnlink Uplink Configuration guration		
Test ID	CC & Mapping (NOTE	ChBw	RB allocation		Modulation	RB allocation
	4)					(NOTE 1)
	PCC/CC1	100	N/A for	this test	DFT-s-OFDM QPSK	Inner Full
1	SCC/CC2	100			-	-
1	SCC/CC3	100			-	-
	SCC/CC4	100			-	-
NOTE 1:	The specific configuration	of each RF	allocation is	s defined in T	Table 6.1-1 for PC2, PC3 a	nd PC4 or Table
	6.1-2 for PC1.					
NOTE 2:	CA Configuration Test cur					
	Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.					
NOTE 3:	NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated BW, only the combination with the lowest PCC ChBW is tested.					ulative aggregated
NOTE 4:	NOTE 4: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj, with CCi or CCj frequencies defined in TS38.508-1 [10].					ient carrier CCJ,
	with CCI of CCJ frequencie		11 1330.308-	· i [ i u].		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals for PCC are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2A.1.2.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.1.2.3.4.3

#### 6.2A.1.2.3.4.2 Test procedure

- 1. Configure PCC and SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.2A.1.2.3.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.2A.1.2.3.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.2A.1.2.3.4.3.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.

- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 7. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP measurements for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.3. After a rotation, allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for UE to find the best beam to use. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 8. Calculate a cumulative distribution function for the measured EIRP values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.2A.1.2.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.2A.1.2.3.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.3.5-1 to Table 6.2A.1.2.3.5-4.

#### Table 6.2A.1.2.3.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
CA_n257I	32.0-TT
CA_n260I	30.0-TT
CA_n260Q	30.0-TT
CA_n261I	32.0-TT
CA_n261Q	32.0-TT

#### Table 6.2A.1.2.3.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)			
CA_n257I	32.0-TT			
CA_n261I	32.0-TT			
CA_n261Q	32.0-TT			

## Table 6.2A.1.2.3.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)			
CA_n257I	11.5-TT			
CA_n260I	8-TT			
CA_n260Q	8-TT			
CA_n261I	11.5-TT			
CA_n261Q	11.5-TT			

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257I	CA_n258	CA_n260I/Q	CA_n261I/Q		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MB₅		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MB₅	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MB₅		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB₅			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MBs	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MB₅	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MB₅	11.5-TT-MBs	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 2	1: MB <sub>s</sub> is the Multiban	d Relaxation fac	tor declared l	by the UE for th	e tested band in	n table A.4.3.9	-3 of TS38.508-2. This
Note 2	declaration shall fulfil the requirements in clause 6.2.1.1.3.3. Note 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant						
Note 3	Note 3: Max allowed sum of MBs over all supported FR2 bands as defined in clause 6.2.1.1.3.3						

# Table 6.2A.1.2.3.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB₅>0 in any FR2 band

#### Table 6.2A.1.2.3.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)			
CA_n257I	25-TT			
CA_n260I	19-TT			
CA_n260Q	19-TT			
CA_n261I	25-TT			
CA_n261Q	25-TT			

#### Table 6.2A.1.2.3.5-5: Test Tolerance (Spherical coverage) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b	
IFF (Quiet Zone size ≤ 30 cm)	2.58 dB	2.58 dB	

## 6.2A.1.2.4 Spherical coverage for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test configuration table is TBD.
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

### 6.2A.1.2.4.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

#### 6.2A.1.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

#### 6.2A.1.2.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

#### 6.2A.1.2.4.4 Test description

Same as in clause 6.2A.1.2.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.2.4.1-1 → use Table 6.2A.1.2.4.4.1-1.
- Instead of Table 6.2A.1.2.1.5-1 to  $5 \rightarrow$  use Table 6.2A.1.2.4.5-1 to 5.

#### Table 6.2A.1.2.4.4.1-1: Test Configuration Table

FFS

#### 6.2A.1.2.4.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.4.5-1 to Table 6.2A.1.2.4.5-4.

#### Table 6.2A.1.2.4.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)		
CA_n257J	32.0-TT		
CA_n260J	30.0-TT		
CA_n261J	32.0-TT		

#### Table 6.2A.1.2.4.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)			
CA_n257J	18.0-TT			
CA_n261J	18.0-TT			

## Table 6.2A.1.2.4.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)		
CA_n257J	11.5-TT		
CA_n260J	8-TT		
CA_n261J	11.5-TT		

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257J	CA_n258	CA_n260J	CA_n261J		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MBs	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB₅			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MBs	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB₅	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 1	I: MB <sub>s</sub> is the Multiban	d Relaxation fac	tor declared b	by the UE for th	e tested band in	n table A.4.3.9	-3 of TS38.508-2. This
	<ul> <li>declaration shall fulfil the requirements in clause 6.2.1.1.3.3.</li> <li>Note 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant</li> <li>Note 3: Max allowed sum of MB<sub>s</sub> over all supported FR2 bands as defined in clause 6.2.1.1.3.3</li> </ul>						

## Table 6.2A.1.2.4.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB₅>0 in any FR2 band

#### Table 6.2A.1.2.4.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)		
CA_n257J	25-TT		
CA_n260J	19-TT		
CA_n261J	25-TT		

#### Table 6.2A.1.2.4.5-5: Test Tolerance (Spherical coverage) (400MHz < Aggregated BW ≤ 800MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

## 6.2A.1.2.5 Spherical coverage for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test configuration table is TBD.
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2A.1.2.5.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

6.2A.1.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.2A.1.2.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

#### 6.2A.1.2.5.4 Test description

Same as in clause 6.2A.1.2.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.2.4.1-1 → use Table 6.2A.1.2.5.4.1-1.
- Instead of Table 6.2A.1.2.1.5-1 to  $5 \rightarrow$  use Table 6.2A.1.2.5.5-1 to 5.

#### Table 6.2A.1.2.5.4.1-1: Test Configuration Table

FFS

#### 6.2A.1.2.5.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.5.5-1 to Table 6.2A.1.2.5.5-4.

#### Table 6.2A.1.2.5.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)		
CA_n257K	32.0-TT		
CA_n260K	30.0-TT		
CA_n261K	32.0-TT		

#### Table 6.2A.1.2.5.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)			
CA_n257K	18.0-TT			
CA_n261K	18.0-TT			

## Table 6.2A.1.2.5.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)		
CA_n257K	11.5-TT		
CA_n260K	8-TT		
CA_n261K	11.5-TT		

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257J	CA_n258	CA_n260J	CA_n261J		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MBs	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB₅			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MBs	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB₅	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 2	Note 1: MB <sub>s</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-3 of TS38.508-2. This						
	declaration shall fulfil the requirements in clause 6.2.1.1.3.3.						
Note 2	lote 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant						
Note 3	te 3: Max allowed sum of MB <sub>s</sub> over all supported FR2 bands as defined in clause 6.2.1.1.3.3						

# Table 6.2A.1.2.5.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB₅>0 in any FR2 band

#### Table 6.2A.1.2.5.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)			
CA_n257K	25-TT			
CA_n260K	19-TT			
CA_n261K	25-TT			

#### Table 6.2A.1.2.5.5-5: Test Tolerance (Spherical coverage) (400MHz < Aggregated BW ≤ 800MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

## 6.2A.1.2.6 Spherical coverage for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test configuration table is TBD.
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2A.1.2.6.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

6.2A.1.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.2A.1.2.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

#### 6.2A.1.2.6.4 Test description

Same as in clause 6.2A.1.2.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.2.4.1-1 → use Table 6.2A.1.2.6.4.1-1.
- Instead of Table 6.2A.1.2.1.5-1 to Table 6.2A.1.2.1.5-5 → use Table 6.2A.1.2.6.5-1 to Table 6.2A.1.2.6.5-5.

### Table 6.2A.1.2.6.4.1-1: Test Configuration Table

#### FFS

#### 6.2A.1.2.6.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.6.5-1 to Table 6.2A.1.2.6.5-4.

#### Table 6.2A.1.2.6.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
CA_n257L	32.0-TT
CA_n260L	30.0-TT
CA_n261L	32.0-TT

#### Table 6.2A.1.2.6.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)		
CA_n257L	18.0-TT		
CA_n261L	18.0-TT		

## Table 6.2A.1.2.6.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)		
CA_n257L	11.5-TT		
CA_n260L	8-TT		
CA_n261L	11.5-TT		

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257L	CA_n258	CA_n260L	CA_n261L		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MBs	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB₅			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MBs	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB₅	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 2	Note 1: MB <sub>s</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-3 of TS38.508-2. This						
	declaration shall fulfil the requirements in clause 6.2.1.1.3.3.						
Note 2	Jote 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant						
Note 3	ote 3: Max allowed sum of MB <sub>s</sub> over all supported FR2 bands as defined in clause 6.2.1.1.3.3						

# Table 6.2A.1.2.6.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB₅>0 in any FR2 band

#### Table 6.2A.1.2.6.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)
CA_n257L	25-TT
CA_n260L	19-TT
CA_n261L	25-TT

#### Table 6.2A.1.2.6.5-5: Test Tolerance (Spherical coverage) (400MHz < Aggregated BW ≤ 800MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

## 6.2A.1.2.7 Spherical coverage for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test configuration table is TBD.
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

#### 6.2A.1.2.7.1 Test purpose

To verify that the spatial coverage of the UE for CA in expected directions is acceptable.

6.2A.1.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

#### 6.2A.1.2.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.1.0.

#### 6.2A.1.2.7.4 Test description

Same as in clause 6.2A.1.2.1.4 with following exceptions:

- Instead of Table 6.2A.1.1.2.4.1-1 → use Table 6.2A.1.2.7.4.1-1.
- Instead of Table 6.2A.1.2.1.5-1 to Table 6.2A.1.2.1.5-5 → use Table 6.2A.1.2.7.5-1 to Table 6.2A.1.2.7.5-5.

## Table 6.2A.1.2.7.4.1-1: Test Configuration Table

#### FFS

#### 6.2A.1.2.7.5 Test requirement

The defined %-tile EIRP in measurement distribution derived in step 8 shall exceed the values specified in Table 6.2A.1.2.7.5-1 to Table 6.2A.1.2.7.5-4.

#### Table 6.2A.1.2.7.5-1: Intra-band Contiguous CA UE spherical coverage for power class 1

Operating band	Min EIRP at 85%-tile CDF (dBm)
CA_n257M	32.0-TT
CA_n260M	30.0-TT
CA_n261M	32.0-TT

#### Table 6.2A.1.2.7.5-2: Intra-band Contiguous CA UE spherical coverage for power class 2

Operating band	Min EIRP at 60%-tile CDF (dBm)		
CA_n257M	18.0-TT		
CA_n261M	18.0-TT		

## Table 6.2A.1.2.7.5-3: Intra-band Contiguous CA UE spherical coverage for power class 3 for single band UE or multiband UE declaring $MB_s = 0$ in all FR2 bands

Operating band	Min EIRP at 50 <sup>t</sup> %-tile CDF (dBm)		
CA_n257M	11.5-TT		
CA_n260M	8-TT		
CA_n261M	11.5-TT		

ID	Supported FR2 bands set	Test requirement (dB) (Note 1)			Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments	
		CA_n257M	CA_n258	CA_n260M	CA_n261M		
1	n257, n258	11.5-TT-MBs				1.25	
2	n257, n260	11.5-TT-MB <sub>s</sub>		8-TT-MB <sub>s</sub>		0.75	Maximum 0.4 dB relaxation allowed for n260
3	n258, n260			8-TT-MBs		0.75	Maximum 0.4 dB relaxation allowed for n260
4	n258, n261				11.5-TT-MB₅	1.25	
5	n260, n261			8-TT-MB₅	11.5-TT-MBs	0.75	No relaxation allowed for n260
6	n257, n258, n260	11.5-TT-MBs		8-TT-MBs		1.75	Maximum 0.4 dB relaxation allowed for n260
7	n257, n258, n261	11.5-TT-MB₅			11.5-TT-MB₅	1.75	
8	n257, n260, n261	11.5-TT-MBs		8-TT-MBs	11.5-TT-MB <sub>s</sub>	1.25	Maximum 0.4 dB relaxation allowed for n260
9	n258, n260, n261			8-TT-MBs	11.5-TT-MB₅	1.25	Maximum 0.4 dB relaxation allowed for n260
10	n257, n258, n260, n261	11.5-TT-MBs		8-TT-MB₅	11.5-TT-MB₅	1.75	Maximum 0.4 dB relaxation allowed for n260
Note 2	Note 1: MB <sub>s</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-3 of TS38.508-2. This						
	declaration shall fulfil the requirements in clause 6.2.1.1.3.3.						
Note 2	ote 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant						
Note 3	te 3: Max allowed sum of MB <sub>s</sub> over all supported FR2 bands as defined in clause 6.2.1.1.3.3						

# Table 6.2A.1.2.7.5-3a: UE spherical coverage for power class 3 for multi band UE declaring MB₅>0 in any FR2 band

#### Table 6.2A.1.2.7.5-4: Intra-band Contiguous CA UE spherical coverage for power class 4

Operating band	Min EIRP at 20%-tile CDF (dBm)
CA_n257M	25-TT
CA_n260M	19-TT
CA_n261M	25-TT

#### Table 6.2A.1.2.7.5-5: Test Tolerance (Spherical coverage) (400MHz < Aggregated BW ≤ 800MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

## 6.2A.2 UE maximum output power reduction for CA

## 6.2A.2.0 Minimum conformance requirements

#### 6.2A.2.0.1 General

The UE is defined to be configured for CA operation when it has at least one of UL or DL configured for CA. In CA operation, the UE may reduce its maximum output power due to higher order modulations and transmit bandwidth configurations. This Maximum Power Reduction (MPR) is defined in subclauses below.

The cumulative aggregated channel bandwidth is defined as the frequency band from the lowest edge of the lowest CC to the upper edge of the highest CC of all UL and DL configured CCs. When the maximum output power of a UE is modified by MPR, the power limits specified in subclause 6.2A.4.0 apply.

The requirements in the following subclauses are only applicable to intra-band contiguous uplink CA, with the aggregated channel bandwidth up to 800 MHz.

### 6.2A.2.0.2 Maximum output power reduction for power class 1

For power class 1, MPR for UL contiguous allocations within the cumulative aggregated bandwidth is defined as:

 $MPR_{C_{CA}} = max(MPR_{WT_{C_{CA}}}, MPR_{narrow})$ 

Where,

 $MPR_{narrow} = 14.4 \text{ dB}$ , when  $BW_{alloc,RB}$  is less than or equal to 1.44 MHz,  $MPR_{narrow} = 10 \text{ dB}$ , when 1.44 MHz <  $BW_{alloc,RB} \le 10.8 \text{ MHz}$ , where  $BW_{alloc,RB}$  is the bandwidth of the RB allocation size.

MPR<sub>WT\_C\_CA</sub> is the maximum power reduction due to modulation orders, transmit bandwidth configurations, and waveform types. MPR<sub>WT\_contiguous</sub> is defined in Table 6.2A.2.2-1.

Table 6.2A.2.0-1: Maximum power reduction (MPR<sub>wt c cA</sub>) for UE power class 1

Waveform Type		Cumulative aggregated channel bandwidth		
		< 400 MHz	≥ 400 MHz and < 800 MHz	≥ 800 MHz and ≤ 1400 MHz
DFT-s-OFDM -	Pi/2 BPSK	≤ 5.5 <sup>1</sup>	7.7 <sup>1</sup>	[8.2]
	QPSK	≤ 6.5 <sup>1</sup>	8.7 <sup>1</sup>	[9.7]
	16 QAM	≤ 6.5	8.7	[9.2]
	64 QAM	≤ 9.0	10.7	[11.2]
CP-OFDM	QPSK	≤ 6.5	8.7	[8.7]
	16 QAM	≤ 6.5	8.7	[8.7]
	64 QAM	≤ 9.0	10.7	[11.2]
NOTE 1: The following condition applies only when the cumulative aggregated BW of the CA configuration ≤				

400MHz. For a contiguous RB allocation in a single CC of the CA configuration, the single CC MPR of subclause 6.2.2.1 applies. The cumulative aggregated bandwidth shall be used as BW<sub>channel</sub> in Tables 6.2.2.1-1 and 6.2.2.1-2. The applicable column in Tables 6.2.2.1-1 and 6.2.2.1-2 shall be determined based on the transmission bandwidth of the CA allocation in relation to the allocation regions defined in the tables.

When different waveform types exist across CCs, the requirement is set by the waveform type used in the configuration with the largest  $MPR_{C_{CA}}$ .

For non-contiguous RB allocations, the following rule for MPR applies:

 $MPR = max(MPR_{C_{CA}}, -10*A + [14.4])$ 

Where:

 $A = N_{RB\_alloc} \ / \ N_{RB\_agg\_C.}$ 

 $N_{RB\_alloc}$  is the total number of allocated UL RBs

N<sub>RB\_agg\_C</sub> is the number of the aggregated RBs within the fully allocated cumulative aggregated channel bandwidth

#### 6.2A.2.0.3 Maximum output power reduction for power class 2

For power class 2, MPR specified in sub-clause 6.2A.2.0.4 applies.

## 6.2A.2.0.4 Maximum output power reduction for power class 3

For power class 3, MPR for UL contiguous allocations within the cumulative aggregated bandwidth is denoted as  $MPR_{C_{CA}}$  and is defined in Table 6.2A.2.0.4-1.

		Cumulative aggregated bandwidth configuration		
		≤ 400 MHz	> 400 MHz and < 800 MHz	≥ 800 MHz and ≤ 1400 MHz
DFT-s-OFDM	Pi/2 BPSK	≤ 5.0 <sup>1</sup>	≤ 7.7 <sup>1</sup>	≤ [8.2]
	QPSK	≤ 5.0 <sup>1</sup>	≤ 7.7 <sup>1</sup>	≤ [8.2]
	16 QAM	≤ 6.5	≤ 8.7	≤ [9.3]
	64 QAM	≤ 9.0	≤ 10.7	≤ [11.2]
CP-OFDM	QPSK	≤ 5.0	≤ 7.5	≤ [8.0]
	16 QAM	≤ 6.5	≤ 8.7	≤ [9.2]
	64 QAM	≤ 9.0	≤ 10.7	≤ [11.2]

Table 6.2A.2.0.4-1: Maximum power reduction (MPRc\_CA) for UE power class 3

When different waveform types exist across CCs, the requirement is set by the waveform type used in the configuration with the highest contiguous MPR.

For non-contiguous RB allocations, the following rule for MPR applies:

 $MPR = max(MPR_{C_{CA}}, -10*A + 7.0)$ 

Where:

 $A = N_{RB\_alloc} \ / \ N_{RB\_agg\_C.}$ 

 $N_{RB\_alloc}$  is the total number of allocated UL RBs

 $N_{RB\_agg\_C}$  is the number of the aggregated RBs within the fully allocated cumulative aggregated channel bandwidth

## 6.2A.2.0.5 Maximum output power reduction for power class 4

For power class 4, MPR specified in sub-clause 6.2A.2.0.4 applies.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2A.2.

## 6.2A.2.1 UE maximum output power reduction for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and intra-band non-contiguous CA are TBD.
- Whether to further divide this test case considering the number of DL CC is FFS
- TP analysis needs further update to reflect the selection of applicable cumulative aggregated BW
- Following aspects are pending RAN4

Minimum requirements for cumulative aggregated bandwidth >=800MHz are within brackets

T(MPR) in 6.2A.4 configured output power is within brackets.

### 6.2A.2.1.1 Test purpose

The number of RB identified in 6.2.2.3 is based on meeting the requirements for the maximum power reduction (MPR) due to Cubic Metric (CM).

#### 6.2A.2.1.2 Test applicability

The requirements of this test apply to all types of NR UE release 15 and forward supporting 2UL CA.

#### 6.2A.2.1.3 Minimum conformance requirements

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2A.2.0.

- 6.2A.2.1.4 Test description
- 6.2A.2.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.2A.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

 Table 6.2A.2.1.4.1-1: Intra-band Contiguous UL CA Test Configuration Table (Power Class 1, MPRnarrow)

			Default	t Conditions				
Test F	Environment as spe	cified in TS 38 5		Normal				
	ause [4.1]							
	Frequencies as spe	cified in TS 38 50	08-1 [10]	Refer to "Test	frequency" column			
	ause [4.3.1.2.3] for				noquonoy column			
classe								
	CC Combination se	tting (aggregated	BW of the	Highest aggre	dated channel band	lwidth of the CA		
	onfiguration) as spe			Highest aggregated channel bandwidth of the CA configuration				
	2-1 and 5.5A.2-2 fo			g				
	width combination s							
	SCS as specified in			120 kHz				
	ł		Test I	Parameters				
Test	CC & Mapping	ChBw(MHz)	Test	DL RB	UL Modulation	UL RB allocation		
ID	(NOTE 2)	. ,	frequency	allocation		(NOTE 1)		
					XG, CA_nXO Conf	iguration		
	PCC/CC1	Default	Low	N/A for this	CP-OFDM	Outer_1RB_Left		
1					64QAM			
	SCC/CC2		Low	test	-	-		
-	PCC/CC1		High		CP-OFDM	Outer_1RB_Right		
2					64QAM			
	SCC/CC2		High		-	-		
_	PCC/CC1		Low		CP-OFDM	7@0		
3			-		64QAM			
	SCC/CC2		Low		-	-		
	PCC/CC1		High		CP-OFDM	7@N <sub>RB</sub> -7		
4					64QAM			
	SCC/CC2		High		-	-		
De	efault Test Setting	s for a CA_nX(D				O)_UL_nXD, CA_nX(D-		
			O)_UL_nX	O Configuratio				
	PCC/CC1	Default	Low	N/A for this	CP-OFDM	Outer_1RB_Left		
					64QAM			
4	SCC1/CC2		Low	test	-	-		
1	Wgap		Max Wgap		N/A	N/A		
	SCC2/CC3		Low		N/A	N/A		
	SCC3/CC4		Low		N/A	N/A		
	PCC/CC1		High		CP-OFDM	Outer ADD Diskt		
			5		64QAM	Outer_1RB_Right		
-	SCC1/CC2		High		-	-		
2	Wgap		Max Wgap		N/A	N/A		
	SCC2/CC3		High		N/A	N/A		
	SCC3/CC4		High		N/A	N/A		
	PCC/CC1		Low		CP-OFDM			
	100/001		2011		64QAM	7@0		
	SCC1/CC2		Low		-	-		
3	Wgap		Max Wgap		N/A			
	SCC2/CC3			1		ΝΙ/Δ		
	0002/000					N/A		
			Low		N/A	N/A		
	SCC3/CC4		Low		N/A N/A			
					N/A N/A CP-OFDM	N/A		
	SCC3/CC4 PCC/CC1		Low High		N/A N/A	N/A N/A		
4	SCC3/CC4 PCC/CC1 SCC1/CC2		Low High High		N/A N/A CP-OFDM 64QAM -	N/A N/A 7@N <sub>RB</sub> -7		
4	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap		Low High High Max Wgap		N/A N/A CP-OFDM 64QAM - N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A		
4	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3		Low High High Max Wgap High		N/A N/A CP-OFDM 64QAM - N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A		
	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4		Low High Max Wgap High High		N/A N/A CP-OFDM 64QAM - N/A N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A N/A		
	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings		Low High Max Wgap High High J_UL_nXD, Ca	A_ <u>nX(D-P)_UL</u>	N/A N/A CP-OFDM 64QAM - N/A N/A N/A N/A N/A CA_nX(E-O)	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A		
	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	for a CA_nX(D-F Default	Low High Max Wgap High High	<b>A_nX(D-P)_UL</b> N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A <b>N/A</b> <b>N/A</b> CP-OFDM	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A N/A UL_nXO Configuration		
	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1		Low High Max Wgap High High I)_UL_nXD, CA	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A N/A N/A CA_nX(E-O)	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A 		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2		Low High Max Wgap High High JUL_nXD, Ca Low	<b>A_nX(D-P)_UL</b> N/A for this test	N/A N/A CP-OFDM 64QAM - N/A N/A N/A <b>N/A</b> <b>N/A</b> <b>N/A</b> CP-OFDM 64QAM	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A N/A _UL_nXO Configuration Outer_1RB_Left -		
	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap		Low High Max Wgap High High D_UL_nXD, CA Low Low Max Wgap	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A _UL_nXO Configuration Outer_1RB_Left - N/A		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3		Low High Max Wgap High High J_UL_nXD, Ca Low Low Max Wgap Low	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A 		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4		Low High Max Wgap High High D_UL_nXD, CA Low Low Max Wgap	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A _UL_nXO Configuration Outer_1RB_Left - N/A N/A N/A N/A		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4		Low High Max Wgap High High J_UL_nXD, Ca Low Low Max Wgap Low	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A N/A N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A 		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4		Low High Max Wgap High J_UL_nXD, Ca Low Max Wgap Low Low	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A UL_nXO Configuration Outer_1RB_Left - N/A N/A N/A N/A		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4		Low High Max Wgap High J_UL_nXD, Ca Low Max Wgap Low Low Low	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A <b>N/A</b> CP-OFDM 64QAM - N/A N/A N/A N/A	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A _UL_nXO Configuration Outer_1RB_Left - N/A N/A N/A N/A		
Defa	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4		Low High Max Wgap High JUL_nXD, C Low Low Max Wgap Low Low Low High High	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A CP-OFDM 64QAM - N/A N/A N/A N/A N/A CP-OFDM	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A UL_nXO Configuration Outer_1RB_Left - N/A N/A N/A N/A		
Defa 1	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 PCC/CC1 SCC1/CC2		Low High Max Wgap High JUL_nXD, C Low Low Max Wgap Low Low Low High High	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A CP-OFDM 64QAM - N/A N/A N/A N/A N/A CP-OFDM	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A UL_nXO Configuration Outer_1RB_Left - N/A N/A N/A N/A		
Defa 1	SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4 SCC4/CC5 PCC/CC1		Low High Max Wgap High High J_UL_nXD, CA Low Low Max Wgap Low Low Low Low Low	N/A for this	N/A N/A CP-OFDM 64QAM - N/A N/A N/A CP-OFDM 64QAM - N/A N/A N/A N/A N/A CP-OFDM 64QAM - -	N/A N/A 7@N <sub>RB</sub> -7 - N/A N/A <b>UL_nXO Configuration</b> Outer_1RB_Left - N/A N/A N/A N/A N/A N/A - N/A - N/A - - - - - - - - - - - - - - - - - - -		

	SCC3/CC4		High		N/A	N/A
	SCC4/CC5		High		N/A	N/A
	PCC/CC1		Low		CP-OFDM	
	100/001		Low		64QAM	7@0
	SCC1/CC2		Low		-	-
3	Wgap		Max Wgap		N/A	N/A
	SCC2/CC3		Low		N/A	N/A
	SCC3/CC4		Low		N/A	N/A
	SCC4/CC5		Low		N/A	N/A
	PCC/CC1		High		CP-OFDM 64QAM	7@N <sub>RB</sub> -7
	SCC1/CC2		High		-	-
4	Wgap		Max Wgap		N/A	N/A
	SCC2/CC3		High		N/A	N/A
	SCC3/CC4		High		N/A	N/A
	SCC4/CC5		High		N/A	N/A
Defa	ault Test Settings	for a CA_nX(D-	I)_UL_nXD, CA	A_nX(D-Q)_UL_	_nXD, CA_nX(G-I)_	UL_nXG Configuration
	PCC/CC1	Default	Low	N/A for this	CP-OFDM 64QAM	Outer_1RB_Left
	SCC1/CC2		Low	test	-	-
	Wgap		Max Wgap		N/A	N/A
1	SCC2/CC3		Low		N/A	N/A
	SCC3/CC4		Low		N/A	N/A
	SCC4/CC5		Low		N/A	N/A
	SCC5/CC6		Low		N/A	N/A
	PCC/CC1		High		CP-OFDM 64QAM	Outer_1RB_Right
	SCC1/CC2		High		-	-
	Wgap		Max Wgap		N/A	N/A
2	SCC2/CC3		High		N/A	N/A
	SCC3/CC4		High		N/A	N/A
	SCC4/CC5		High		N/A	N/A
	SCC5/CC6		High		N/A	N/A
	PCC/CC1		Low		CP-OFDM 64QAM	7@0
	SCC1/CC2		Low		-	-
	Wgap		Max Wgap		N/A	N/A
3	SCC2/CC3		Low		N/A	N/A
	SCC3/CC4		Low		N/A	N/A
	SCC4/CC5		Low		N/A	N/A
	SCC5/CC6		Low		N/A	N/A
	PCC/CC1		High		CP-OFDM 64QAM	7@N <sub>RB</sub> -7
	SCC1/CC2		High		-	-
	Wgap		Max Wgap		N/A	N/A
4	SCC2/CC3		High		N/A	N/A
	SCC3/CC4		High		N/A	N/A
	SCC4/CC5		High		N/A	N/A
	SCC5/CC6		High		N/A	N/A
	0000/000			on is defined in		1 1// 1

# Table 6.2A.2.1.4.1-2: Intra-band Contiguous UL CA Test Configuration Table (Power Class 1, single CC MPR requirement)

			Default C	onditions				
	Environment as specif ause [4.1]	ied in TS 38.508-′	1 [10]	Normal				
	Frequencies as specif ause [4.3.1.2.3] for dif			Lowest range,	Highest range			
Test C config and 5.	CC Combination settin juration) as specified .5A.2-2 for the CA Co ination sets supported	ng (aggregated BV in Table 5.5A.1-1, nfiguration across	V of the CA 5.5A.2-1	Highest aggreg configuration	pated channel bandwic	Ith of the CA		
	SCS as specified in Ta			120 kHz				
	•		Test Pa	rameters				
Test	CC & Mapping	ChBw(MHz)	Test	DL RB	UL Modulation	UL RB allocation		
ID	(NOTE 2)		frequency	allocation				
Defa	• •	a CA nXG. CA	nXO Configu	ration (Cumulat	tive aggregated BWc	hannel <= 200MHz)		
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM PI/2 BPSK	Outer_Full		
	SCC/CC2			test	-	-		
2	PCC/CC1				DFT-s-OFDM QPSK	Inner_Full_Region1		
	SCC/CC2				-	-		
	<b>Default Test Setting</b>	is for a CA_nXD	Configuratio	n (Cumulative a	ggregated BWchann	el <= 400MHz)		
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM PI/2 BPSK	Outer_Full		
	SCC/CC2			test	-	-		
2	PCC/CC1				DFT-s-OFDM PI/2 BPSK	Inner_Full_Region1		
	SCC/CC2				-	-		
3	PCC/CC1				DFT-s-OFDM QPSK	Inner_Full_Region1		
	SCC/CC2				-	-		
NOTE	with CCi or CCj f	CČ/CCj means PC frequencies define	C is on comp d in TS38.508	onent carrier CC 3-1 [10].	ble 6.1-2. i and SCC is on comp ts half Pi BPSK in FR1			

Table 6.2A.2.1.4.1-3: Intra-band Contiguous UL CA Test Configuration Table (Power Class 1,  $MPR_{C_CA}$ )

			Default Cond	litions			
Test E [4.1]	Environment as spe	ecified in TS 38.508-	1 [10] subclause	Normal			
		cified in TS 38.508- A bandwidth classes		For intra-band r	contiguous CA: Mid ra non-contiguous CA: L	owest range with	
T				Max Wgap, Highest range with Max Wgap. Highest aggregated channel bandwidth of the CA			
		etting (aggregated B) ad in Table 5.5A.1-1,		configuration	ated channel bandwid	ith of the CA	
5.5A.2		figuration across bar		connguration			
	SCS as specified in			120 kHz			
Test	CC& Mapping	ChBw(MHz)	Test Parame	eters DL RB	UL Modulation	UL RB	
ID	(NOTE 2)		frequency	allocation		allocation	
De		s for a CA nYB CA		Configuration (80	0MHz <= Cumulativ	e andregated	
De	adit rest betting		BWchannel <= 1			e aggi egaleu	
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
I	SCC/CC2			test	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
2	PCC/CC1				DFT-s-OFDM QPSK	Outer_Full	
2	SCC/CC2				DFT-s-OFDM QPSK	Outer_Full	
3	PCC/CC1				DFT-s-OFDM 16QAM	Outer_Full	
-	SCC/CC2				DFT-s-OFDM 16QAM	Outer_Full	
4	PCC/CC1				CP-OFDM 16QAM	Outer_Full	
	SCC/CC2				CP-OFDM 16QAM	Outer_Full	
5	PCC/CC1 SCC/CC2				CP-OFDM 64QAM CP-OFDM	Outer_Full Outer_Full	
					64QAM		
Defa					aggregated BWcha		
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
	SCC/CC2			test	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
2	PCC/CC1				CP-OFDM 16QAM	Outer_Full	
	SCC/CC2				CP-OFDM 16QAM	Outer_Full	
3	PCC/CC1 SCC/CC2				CP-OFDM 64QAM CP-OFDM	Outer_Full Outer_Full	
					64QAM		
Defa					aggregated BWcha		
1	PCC/CC1	200MHz	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
I	SCC/CC2	400MHz		test	DFT-s-OFDM Pi/2 BPSK	Outer_Full	
2	PCC/CC1	200MHz			CP-OFDM 16QAM	Outer_Full	
2	SCC/CC2	400MHz			CP-OFDM 16QAM	Outer_Full	
3	PCC/CC1	200MHz			CP-OFDM 64QAM	Outer_Full	
	SCC/CC2	400MHz			CP-OFDM 64QAM	Outer_Full	
Defa					aggregated BWchan		
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full	

SCC/CC2         DFT-s-OFDM         Outer_Full           PCC/CC1         SCC/CC2         CP-OFDM         Outer_Full           PCC/CC1         SCC/CC2         CP-OFDM         Outer_Full           BCC/CC2         SCC/CC2         CP-OFDM         Outer_Full           SCC/CC2         Default Test Settings for a CA_nXD Configuration (Cumulative aggregated SWChannel - 400MHz)         Outer_Full           Default Test Settings for a CA_nXD Configuration (Cumulative aggregated SWChannel - 400MHz)         Outer_Full           SCC/CC2         200MHz         NA for this         P/2 EPSK           PCC/CC1         100MHz         Default         NA for this         P/2 EPSK           PCC/CC1         100MHz         Default         NA for this         P/2 EPSK         Outer_Full           SCC/CC2         200MHz         Eest         P/2 EPSK         Outer_Full         GA_AND           J         SCC/CC2         200MHz         Eest         P/2 EPSK         Outer_Full         GA_AND           J         SCC/CC2         200MHz         EcorrEdM         Outer_Full         GA_AND         Outer_Full           J         SCC/CC2         200MHz         EcorrEdM         NA         NA         NA           J         SCCC/CC2         Default				1			
2         PCC/CC1         Default Test Settings for a CA_nXD Configuration (Cumulative aggregated Bwchannel < 400MHz)		SCC/CC2			test	DFT-s-OFDM Pi/2 BPSK	Outer_Full
2         SCC/CC2         16QAM         CP-OFDM         Outer_Full           3         SCC/CC2         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           1         SCC/CC2         Default Test Settings for a CA_nXD Configuration (Cumulative aggregated EWchannel < 400MHz)		PCC/CC1					Outer Full
SCC/CC2         CP-OFUM         Outer_Ful GAUM           3         SCC/CC2         160,MM         CP-OFDM         Outer_Ful GAUM           0         SCC/CC2         100,MHz         Default Test Settings for a CA_nXD Configuration (Cumulative aggregated Bwchannel < 400,HLZ)	2						
3         PCC/CC1         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         Default Test Settings for a CA_NXD Configuration (Cumulative aggregated BWChannel < 400MHz)	2	SCC/CC2					Outer_Full
3         EddAM							
3         SCC/CC2         CP-OFDM         Outer_Full           PCC/CC1         100MHz         Default         N/A for this         PFC-FOM         Outer_Full           2         SCC/CC2         200MHz         test         DFT-s-OFDM         Outer_Full           2         SCC/CC2         200MHz         test         DFT-s-OFDM         Outer_Full           3         SCC/CC2         200MHz         test         DFT-s-OFDM         Outer_Full           4         PCC/CC1         100MHz         CP-OFDM         Outer_Full         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full         Outer_Full           4         PCC/CC1         100MHz         CP-OFDM         Outer_Full         Outer_Full           0         U_nXO Configuration (800MHz <= Cumulative aggregated BWchannel < 400MHz)	_	FCC/CC1					Outer_Fuil
Default Test Settings for a CA_NXD Configuration (Cumulative aggregated BWChannel 4 400MHz)         Outer_Full           PCC/CC1         100MHz         Default         N/A for this         DFT-s-OFDM         Outer_Full           PCC/CC1         100MHz         test         DFT-s-OFDM         Outer_Full           PCC/CC1         100MHz         test         DFT-s-OFDM         Outer_Full           PCC/CC1         100MHz         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full           6         PCC/CC1         100MHz         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full           6         PCC/CC1         100MHz         CP-OFDM         Outer_Full           6         SCC/CC2         200MHz         CP-OFDM         Outer_Full           9         SCC/CC2         200MHz         CP-OFDM         Outer_Full           1         SCC/CC2         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         SCC/CC2         SCC/CC2         Vigap         N/A         N/A         N/A           2         SCC/CC2         Wgap         <	3	SCC/CC2					Outer_Full
PCC/CC1         100MHz         Default         N/A for this         DFT-s-OFDM         Outer_Full           2         SCC/CC2         200MHz         test         PCC/CC1         100MHz           2         SCC/CC2         200MHz         test         PCC/PDM         Outer_Full           3         SCC/CC2         200MHz         PCC/CC1         100MHz         CP-OFDM         Outer_Full           4         PCC/CC1         100MHz         PCC/CC1         00Hz         CP-OFDM         Outer_Full           5         SCC/CC2         200MHz         PCC/CC1         00Hz         CP-OFDM         Outer_Full           640AM         CP-OFDM         Outer_Full         640AM         CP-OFDM         Outer_Full           0_UL_nXO Configuration (800MHz <= Cumulative aggregated EWchannel <= 1400MHz)							
Image: science in the section of the sectio							
1         SCC/CC2         200MHz         test         DFT-s-CFDM         Outer_Full           2         SCC/CC2         200MHz         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           4         PCC/CC1         100MHz         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           5         SCC/CC2         200MHz         CP-OFDM         Outer_Full         CP-OFDM         Outer_Full           6         Default         Default         Default         NA (CA nXD-O)         Outer_Full         PC/CCA         Outer_Full           1         Wgap         SCC2/CC3         V/A         N/A         N/A         N/A           2         Wgap         SCC1/CC2         V/A         N/A         N/A         N/A           3         SCC1/CC2         V/G2         V/A         N/A         N/A         N/A           4         Wgap         SCC2/CC3         V/A         N/A         N/A         N/A		PCC/CCT	TUUIMIHZ	Delault	N/A IOF this		Outer_Full
PCC/CC1         100MHz           2         SCC/CC2         200MHz           3         SCC/CC2         200MHz           3         SCC/CC2         200MHz           0         Default Test Settings for a CA_nX(D-G)_UL_nXD, CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_NX(D-O)_UL	1	SCC/CC2	200MHz		test		Outer_Full
2         SCC/CC2         200MHz         160AM         Outer_Full           3         PCC/CC1         100MHz         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full           0         Default Test Settings for a CA_NX(D-G)_UL_NXD, CA_AXD-G)_UL_NXD, CA_AXD-G)_UU_NXD, CA_AXD-G)		200/00/					
2         SCC/CC2         200MHz         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full           3         SCC/CC2         200MHz         CP-OFDM         Outer_Full           9         Default Test Settings for a CA_nX(D-G)_UL_nXD, CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_nX(D-P)_UL_NXD, CA_nX(D-P)_UL_NXD, CA_nX(E-O)_UL_NXD, CA_NX(E-O)_UL_NXD		PCC/CC1	100MHz				Outer_Full
3         16Q-AM	2	SCC/CC2	200MHz				Outer Full
3         SCC/CC2         200MHz         640AM         C           Default Test Settings for a CA_nX(D-G)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-O)_UL_nXD, CA_nX(D-G)_UL_nXD, CA_N							
3         SCC/CC2         200MHz         CP-OFDM 64QAM         Outer,Full 64QAM           Default Test Settings for a CA_nX(D-G)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-O)_UL_nXD, CA_nX(D-P)_UL_nXD,		PCC/CC1	100MHz				Outer_Full
Default Test Settings for a CA_NZ(D-G)_UL_NXD, CA_NZ(D-G)_UL_NXD, CA_NX(D-O)_UL_NXD, CA_NX(D-O)_UU-F, UII           1         Wgap         SCC1/CC2         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         Wgap         SCC2/CC3         N/A         N/A         N/A           2         SCC1/CC2         DFT-s-OFDM         Outer_Full         QPSK         N/A         N/A           2         Wgap         SCC1/CC2         DFT-s-OFDM         Outer_Full         QPSK         N/A         N/A           2         Wgap         SCC1/CC2         DFT-s-OFDM         Outer_Full         QPSK         N/A         N/A           3         Wgap         SCC1/CC2         N/A         N/A         N/A         N/A           4         SCC3/CC4         N/A         N/A         N/A         N/A         N/A           4         SCC3/CC4         N/A         N/A         N/A         N/A         N/A           5         SCC1/CC2	3	800/000	2001417				Outor Full
Default Test Settings for a CA_nX(D-G)_UL_nX0, CA_nX(D-G)_UL_nX0, CA_nX(D-O)_UL_nX0, CA_NX(D-U)_UL_NX0,		300/002	20010172				Outer_Full
O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWChannel <= 1400MHz)         Outer_Full         Outer_Full           1         SCC1/CC2         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         Wgap         N/A         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           PCC/CC1         SCC1/CC2         N/A         N/A           SCC1/CC2         SCC1/CC2         DFT-s-OFDM         Outer_Full           QPSK         OUter_Full         QPSK         DFT-s-OFDM         Outer_Full           QPSK         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           Mgap         SCC1/CC2         N/A         N/A         N/A           Mgap         SCC1/CC2         N/A         N/A         N/A           Mgap         SCC1/CC2         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A         N/A	De	fault Test Setting	s for a CA nX(D-G)	UL nXD, CA nX	(D-G) UL nXG,		XD, CA nX(D-
SCC1/CC2         Pi/2 BPSK         —           1         Wgap         SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           PCC/CC1         SCC1/CC2         SCC1/CC2         SCC1/CC2           2         SCC1/CC2         SCC1/CC2         SCC1/CC2           2         SCC1/CC2         SCC1/CC2         SCC1/CC2           3         SCC3/CC4         N/A         N/A           PCC/CC1         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           3         SCC3/CC4         SCC1/CC2         N/A         N/A           4         SCC3/CC4         SCC1/CC2         N/A         N/A           4         SCC2/CC3         SCC1/CC2         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           5         SCC1/CC2         SC				MHz <= Cumulat			MHz)
I         SCC1/CC2         test         DFT-s-OFDM         Outer_Full           N/A         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full         OPT-s-OFDM         Outer_Full           SCC1/CC2         Wgap         N/A         N/A         N/A           SCC1/CC2         Wgap         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           Mgap         SCC2/CC3         SCC1/CC2         N/A         N/A           Mgap         SCC2/CC3         SCC3/CC4         N/A         N/A           Vgap         SCC2/CC3         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC2/CC3         N/A         N/A         N/A           SCC2/CC3         SCC3/CC4 <t< td=""><td></td><td>PCC/CC1</td><td>Default</td><td>Default</td><td>N/A for this</td><td></td><td>Outer_Full</td></t<>		PCC/CC1	Default	Default	N/A for this		Outer_Full
1         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           2         PCC/CC1         N/A         N/A         N/A           2         SCC1/CC2         DFT-s-OFDM         Outer_Full         QPSK           3         SCC2/CC3         N/A         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           8         SCC2/CC3         N/A         N/A         N/A           9         SCC1/CC2         N/A         N/A         N/A           9         SCC1/CC2         N/A         N/A         N/A           9         SCC1/CC2         DFT-s-OFDM         Outer_Full         16QAM           9         SCC1/CC2         N/A         N/A         N/A           9         SCC1/CC2         N/A         N/A         N/A           16QAM         N/A         N/A         N/A         N/A           9         SCC1/CC2         N/A         N/A         N/A           16QAM         N/A         N/A         N/A         N/A           9         SCC1/CC2         N/A         N/A         N/A           9		SCC1/CC2			tost		Outor Full
Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full           QPSK         DFT-s-OFDM         Outer_Full           QPSK         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         SCC1/CC2         DFT-s-OFDM           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         SCC1/CC3         N/A         N/A           Wgap         SCC1/CC2         N/A         N/A           Wgap         SCC1/CC2         N/A         N/A           V/A         SCC1/CC2         N/A         N/A           V/A         SCC3/CC4         N/A         N/A           V/A         SCC1/CC2         N/A         N/A           SCC1/CC2         SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A </td <td>1</td> <td>3001/002</td> <td></td> <td></td> <td>lesi</td> <td></td> <td>Outer_Full</td>	1	3001/002			lesi		Outer_Full
SCC2/CC3 SCC3/CC4         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full QPSK           Wgap         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           Wgap         SCC1/CC2         N/A         N/A           SCC1/CC2         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           SCC1/CC2         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A	•	Wgap					N/A
2         PCC/CC1         DFT-s-OFDM         Outer_Full           2         Wgap         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           Vgap         SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           Vgap         SCC1/CC2         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC3/CC4         N/A         N/A           SCC2/CC3         SCC3/CC4         N/A						N/A	N/A
2         SCC1/CC2         Outer_Full           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         PCC/CC1         DFT-s-OFDM         Outer_Full           9         SCC1/CC2         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           8         SCC1/CC2         N/A         N/A           9         SCC2/CC3         N/A         N/A           8         SCC2/CC3         N/A         N/A           9         SCC2/CC3         N/A         N/A           9         SCC1/CC2         N/A         N/A           16QAM         Outer_Full         16QAM           16QAM         Outer_Full         16QAM           N/A         N/A         N/A           N/A         N/A         N/A           N/A         N/A         N/A           SCC1/CC2         N/A         N/A           5         SCC1/CC1         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A           5         SCC2/CC3         N/A         N/A           5         SCC2/CC3         N/A						N/A	
2         SCC1/CC2         DFT-s-OFDM         Outer_Full           3         SCC2/CC3         N/A         N/A           4         PCC/CC1         DFT-s-OFDM         Outer_Full           3         Wgap         SCC1/CC2         DFT-s-OFDM         Outer_Full           3         SCC1/CC2         DFT-s-OFDM         Outer_Full         16QAM           3         Wgap         SCC2/CC3         N/A         N/A         N/A           3         SCC1/CC2         DFT-s-OFDM         Outer_Full         16QAM           4         SCC2/CC3         SCC2/CC3         N/A         N/A         N/A           5         SCC2/CC3         SCC2/CC3         N/A         N/A         N/A           5         SCC2/CC3         SCC2/CC3         N/A         N/A         N/A           6         Wgap         SCC2/CC3         N/A         N/A         N/A           5         SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           6         Wgap         SCC2/CC3         N/A         N/A         N/A           5         SCC2/CC3         SCC2/CC3         N/A         N/A         N/A           5         SCC2/CC3		PCC/CC1					Outer_Full
2         QPSK         -           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full           16QAM         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           SCC1/CC2         N/A         N/A           3         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           YA         SCC1/CC2         N/A         N/A           A         SCC1/CC2         N/A         N/A           YA         SCC1/CC2         N/A         N/A           4         Wgap         SCC1/CC2         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           SCC1/CC2         SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A         N/A <td></td> <td>SCC1/CC2</td> <td></td> <td></td> <td></td> <td></td> <td>Outer Full</td>		SCC1/CC2					Outer Full
SCC2/CC3         N/A         N/A           SCC3/CC4         PCC/CC1         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full           16QAM         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         N/A         N/A           SCC1/CC2         N/A         N/A           Vgap         SCC1/CC2         N/A           SCC1/CC2         N/A         N/A           Wgap         SCC2/CC3         N/A           SCC1/CC2         N/A         N/A           Vgap         SCC1/CC2         N/A           SCC1/CC2         N/A         N/A           SCC3/CC4         N/A         N/A           SCC1/CC2         N/A         N/A <tr< td=""><td>2</td><td>0001/002</td><td></td><td></td><td></td><td></td><td></td></tr<>	2	0001/002					
SCC3/CC4         N/A         N/A           PCC/CC1         DFT-s-OFDM         Outer_Full           3         SCC1/CC2         DFT-s-OFDM         Outer_Full           3         Wgap         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full         16QAM           SCC1/CC2         N/A         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full         16QAM           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A           SCC1/CC2         SCC1/CC2         N/A         N/A           SCC2/CC3         SCC3/CC4							
B         PCC/CC1         DFT-s-OFDM         Outer_Full           3         SCC1/CC2         DFT-s-OFDM         Outer_Full           4         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full         16QAM           Mgap         SCC1/CC2         N/A         N/A           SCC2/CC3         SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC3/CC4         N/A         N/A           PCC/CC1         SCC3/CC4         N/A         N/A           SCC2/CC3         SCC1/CC2         CP-OFDM         Outer_Full           64QAM         SCC3/CC4         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           SCC3/CC4							
3         3         16QAM							
3         SCC1/CC2         DFT-s-OFDM         Outer_Full           3         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           4         SCC1/CC2         N/A         N/A         N/A           4         SCC1/CC2         CP-OFDM         Outer_Full         16QAM           5         SCC1/CC2         N/A         N/A         N/A           4         Wgap         Outer_Full         16QAM         Outer_Full           5         SCC1/CC2         N/A         N/A         N/A           5         SCC2/CC3         N/A         N/A         N/A           6         SCC1/CC2         N/A         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           5         SCC1/CC2         N/A         N/A         N/A           64QAM         Outer_Full         64QAM         N/A         N/A           7         SCC3/CC4         N/A         N/A         N/A           8         SCC3/CC3         N/A         N/A         N/A           9         SCC3/CC4         N/A         N/A         N/A           8		PCC/CC1					Outer_Full
3         16QAM         -           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           PCC/CC1         N/A         N/A           BCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           PCC/CC1         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC3/CC4         N/A         N/A           N/A         N/A         N/A           SCC3/CC4         N/A         N/A           N/A         N/A         N/A           SCC3/CC4         N/A         N/A           SCC3/CC4         N/A         N/A <td></td> <td>SCC1/CC2</td> <td></td> <td></td> <td></td> <td></td> <td>Outer Full</td>		SCC1/CC2					Outer Full
SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         N/A         N/A           SCC1/CC2         CP-OFDM         Outer_Full           16QAM         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           SCC2/CC3         N/A         N/A           SCC1/CC2         N/A         N/A           Vgap         N/A         N/A           SCC3/CC4         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration         N/A           (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)	3						
SCC3/CC4         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full           1         SCC1/CC2         CP-OFDM         Outer_Full           1         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full           64QAM         CP-OFDM         Outer_Full           64QAM         N/A         N/A           SCC1/CC2         N/A         N/A           Vgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC2/CC3         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           N/A         N/A         N/A           SCC3/CC4         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration           N/A         N/A         N/A           N/A         N/A         N/A           SCC3/CC4 <td></td> <td></td> <td></td> <td></td> <td></td> <td>N/A</td> <td></td>						N/A	
4       PCC/CC1       Outer_Full         4       SCC1/CC2       CP-OFDM       Outer_Full         4       Wgap       N/A       N/A         SCC2/CC3       N/A       N/A       N/A         SCC3/CC4       N/A       N/A       N/A         PCC/CC1       N/A       N/A       N/A         SCC1/CC2       SCC1/CC2       Outer_Full       64QAM         SCC1/CC2       N/A       N/A       N/A         5       SCC1/CC2       N/A       N/A         5       SCC2/CC3       N/A       N/A         SCC2/CC3       N/A       N/A       N/A         SCC2/CC3       SCO       N/A       N/A         SCC2/CC3       SCO       N/A       N/A         SCC2/CC3       SCO       N/A       N/A         SCC2/CC3       SCO       SCO       SCO <tr tr="">        SCC1/C</tr>							
4         Intersection         Intersection         Intersection         Intersection           4         Wgap         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           PCC/CC1         N/A         N/A         N/A           SCC1/CC2         N/A         N/A         N/A           SCC2/CC3         SCC3/CC4         N/A         N/A           Default         Test Settings for a CA_nx(D-H)_UL_nxD, CA_nx(D-P)_UL_nxD, CA_nx(E-O)_UL_nxO Configuration         N/A           (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)							
4         SCC1/CC2         Outer_Full           4         Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full           64QAM         CP-OFDM         Outer_Full           64QAM         Outer_Full         64QAM           SCC1/CC2         Vgap         N/A         N/A           5         SCC2/CC3         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)		PCC/CC1					Outer_Full
4         16QAM         -           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full           64QAM         CP-OFDM         Outer_Full           5         CP-OFDM         Outer_Full           64QAM         N/A         N/A           SCC1/CC2         Vgap         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO configuration         N/A         N/A           1         PCC/CC1         Default         Default         Default         Default           1         SCC1/CC2         V/A         N/A for this         DFT-s-OFDM         Outer_Full		SCC1/CC2					Outer Full
Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           PCC/CC1         CP-OFDM         Outer_Full           64QAM         64QAM         0/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC1/CC2         N/A         N/A           Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration         N/A           (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)	4	0001/002					
SCC3/CC4       N/A       N/A         PCC/CC1       CP-OFDM       Outer_Full         SCC1/CC2       CP-OFDM       Outer_Full         Wgap       N/A       N/A         SCC2/CC3       N/A       N/A         SCC3/CC4       N/A       N/A         Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration       N/A         (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)		Wgap					N/A
PCC/CC1         CP-OFDM         Outer_Full           5         SCC1/CC2         CP-OFDM         Outer_Full           64QAM         CP-OFDM         Outer_Full           64QAM         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration         N/A           (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)						N/A	N/A
5         SCC1/CC2         G4QAM         CP-OFDM         Outer_Full           5         Wgap         N/A         N/A         N/A           SCC2/CC3         N/A         N/A         N/A           SCC3/CC4         N/A         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration         N/A         N/A           1         PCC/CC1         Default         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         SCC1/CC2         test         DFT-s-OFDM         Outer_Full							
5       SCC1/CC2       CP-OFDM       Outer_Full         5       Wgap       N/A       N/A         SCC2/CC3       N/A       N/A       N/A         SCC3/CC4       N/A       N/A       N/A         Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)		PCC/CC1					Outer_Full
5         64QAM           Wgap         N/A           SCC2/CC3         N/A           SCC3/CC4         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)           PCC/CC1         Default         Default         N/A for this           PCC/CC1         Default         Default         N/A for this           SCC1/CC2         test         DFT-s-OFDM         Outer_Full		SCC1/CC2					
Wgap         N/A         N/A           SCC2/CC3         N/A         N/A           SCC3/CC4         N/A         N/A           Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)	5	3001/002					
SCC2/CC3     N/A     N/A       SCC3/CC4     N/A     N/A       Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)	~	Wgap					N/A
Default Test Settings for a CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(E-O)_UL_nXO Configuration (800MHz <= Cumulative aggregated BWchannel <= 1400MHz)           PCC/CC1         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         SCC1/CC2         test         DFT-s-OFDM         Outer_Full		SCC2/CC3					
(800MHz <= Cumulative aggregated BWchannel <= 1400MHz)           PCC/CC1         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         SCC1/CC2         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full							
PCC/CC1         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full           1         SCC1/CC2         Default         Default         N/A for this         DFT-s-OFDM         Outer_Full	Defa	ault Test Settings					Configuration
1 SCC1/CC2 Pi/2 BPSK test DFT-s-OFDM Outer_Full							Outer Full
1 SCC1/CC2 test DFT-s-OFDM Outer_Full		100/001	Delault	Delault			
Pi/2 BPSK	1	SCC1/CC2			test		Outer_Full
		]				Pi/2 BPSK	

	14/202			1	NI/A	N1/A
	Wgap SCC2/CC3				N/A N/A	N/A N/A
					N/A N/A	N/A
	SCC3/CC4				N/A N/A	N/A N/A
	SCC4/CC5 PCC/CC1					
					DFT-s-OFDM QPSK	Outer_Full
_	SCC1/CC2				DFT-s-OFDM QPSK	Outer_Full
2	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	PCC/CC1				DFT-s-OFDM	Outer_Full
	SCC1/CC2				16QAM DFT-s-OFDM	Outer_Full
~					16QAM	
3	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2				CP-OFDM 16QAM	Outer_Full
4	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
					64QAM	
	SCC1/CC2				CP-OFDM	Outer_Full
-					64QAM	<u>-</u>
5	Wgap					N/A
5	Wgap SCC2/CC3				64QAM N/A	N/A
5	SCC2/CC3				64QAM N/A N/A	N/A N/A
5	SCC2/CC3 SCC3/CC4				64QAM N/A N/A N/A	N/A N/A N/A
	SCC2/CC3 SCC3/CC4 SCC4/CC5	for a CA_nX(D-I)_U	JL_nXD, CA_nX(I	D-Q)_UL_nXD, CA	64QAM N/A N/A N/A N/A	N/A N/A N/A N/A
	SCC2/CC3 SCC3/CC4 SCC4/CC5	for a CA_nX(D-I)_U (800MHz <= Cumu			64QAM N/A N/A N/A N/A A_ <b>nX(G-I)_UL_nXG</b>	N/A N/A N/A N/A
	SCC2/CC3 SCC3/CC4 SCC4/CC5				64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM	N/A N/A N/A N/A
	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings	(800MHz <= Cum	ulative aggregate	d BWchannel <=	64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM	N/A N/A N/A N/A Configuration
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK	N/A N/A N/A Configuration Outer_Full Outer_Full
	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full
De	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC2/CC3 SCC3/CC4	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4 SCC3/CC4	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4 SCC3/CC4 SCC4/CC5 SCC5/CC6	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A DFT-s-OFDM QPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK N/A DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A N/A DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A N/A N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC3/CC4 SCC4/CC5 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A A_N/A N/A DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A DFT-s-OFDM QPSK N/A N/A N/A DFT-s-OFDM QPSK N/A DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A N/A DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A
<b>De</b>	SCC2/CC3 SCC3/CC4 SCC4/CC5 fault Test Settings PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5 SCC3/CC4 SCC4/CC5 SCC5/CC6 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	(800MHz <= Cum	ulative aggregate	<b>d BWchannel &lt;=</b> N/A for this	64QAM N/A N/A N/A N/A A_nX(G-I)_UL_nXG 1400MHz) DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A N/A N/A N/A DFT-s-OFDM QPSK DFT-s-OFDM QPSK N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Configuration Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full N/A N/A

	PCC/CC1				CP-OFDM	Outer_Full
	SCC1/CC2				16QAM CP-OFDM	Outer_Full
4	Wgap				16QAM N/A	N/A
4	vvyap					
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	SCC5/CC6				N/A	N/A
	PCC/CC1				CP-OFDM 64QAM	Outer_Full
	SCC1/CC2				CP-OFDM 64QAM	Outer_Full
5	Wgap				N/A	N/A
-	SCC2/CC3				N/A	N/A
ŀ	SCC3/CC4				N/A	N/A
ł						
	SCC4/CC5				N/A	N/A
	SCC5/CC6				N/A	N/A
Defau	ult Test Settings fo		UL_nXD, CA_nX(D gregated BWchan		nfiguration (400MH	z <= Cumulativo
	PCC/CC1	200MHz	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full
1	SCC1/CC2	200MHz		test	DFT-s-OFDM Pi/2 BPSK	Outer_Full
	Wgap	190MHz			N/A	N/A
ľ	SCC2/CC3	100MHz	1		N/A	N/A
-	SCC3/CC4	100MHz			N/A	N/A
2	PCC/CC1	200MHz	-		CP-OFDM 16QAM	Outer_Full
	SCC1/CC2	200MHz	-		CP-OFDM 16QAM	Outer_Full
-	Wgap	190MHz			N/A	N/A
ŀ	SCC2/CC3	100MHz	_		N/A	N/A
			_			
	SCC3/CC4	100MHz	_		N/A	N/A
	PCC/CC1	200MHz			CP-OFDM 64QAM	Outer_Full
_		2001/11-			CP-OFDM 64QAM	Outer_Full
3	SCC1/CC2	200MHz				
3		190MHz	_		N/A	N/A
3	Wgap	190MHz	_		N/A	
3	Wgap SCC2/CC3	190MHz 100MHz	-		N/A N/A	N/A
	Wgap SCC2/CC3 SCC3/CC4	190MHz 100MHz 100MHz r a CA_nX(D-G)_l			N/A	N/A N/A
	Wgap SCC2/CC3 SCC3/CC4 Ilt Test Settings fo	190MHz 100MHz 100MHz r a CA_nX(D-G)_U ag	gregated BWchan	nel <800MHz)	N/A N/A N/A nfiguration (400MH:	N/A N/A z <= Cumulativ
	Wgap SCC2/CC3 SCC3/CC4 ult Test Settings fo PCC/CC1	<u>190MHz</u> <u>100MHz</u> <b>r a CA_nX(D-G)_U</b> ag 100MHz		nel <800MHz) N/A for this	N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK	N/A N/A z <= Cumulative Outer_Full
	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2	<u>190MHz</u> <u>100MHz</u> <b>r a CA_nX(D-G)_l</b> <u>ag</u> 100MHz 100MHz	gregated BWchan	nel <800MHz)	N/A N/A nfiguration (400MH DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK	N/A N/A z <= Cumulative Outer_Full Outer_Full
Defau	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap	<u>190MHz</u> <u>100MHz</u> <b>r a CA_nX(D-G)_U</b> ag 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM	N/A N/A z <= Cumulative Outer_Full
Defau	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap	190MHz 100MHz <b>100MHz</b> <b>r a CA_nX(D-G)_l</b> ag 100MHz 100MHz 190MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A nfiguration (400MH; DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A
Defau	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	190MHz 100MHz <b>r a CA_nX(D-G)_U</b> <b>ag</b> 100MHz 100MHz 190MHz 200MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A nfiguration (400MH; DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A
Defau	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap	190MHz 100MHz <b>100MHz</b> <b>r a CA_nX(D-G)_l</b> ag 100MHz 100MHz 190MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH; DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	190MHz 100MHz <b>100MHz</b> <b>r a CA_nX(D-G)_U</b> <b>ag</b> 100MHz 100MHz 190MHz 200MHz 200MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A N/A
Defau	Wgap SCC2/CC3 SCC3/CC4 Ilt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2	190MHz 100MHz r a CA_nX(D-G)_U ag 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Ilt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap	190MHz 100MHz r a CA_nX(D-G)_U ag 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	190MHz 100MHz r a CA_nX(D-G)_U ag: 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 100MHz 200MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC2/CC3 SCC3/CC4	190MHz 100MHz r a CA_nX(D-G)_u ag: 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 100MHz 200MHz 200MHz 200MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	190MHz 100MHz r a CA_nX(D-G)_L ag: 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 200MHz 200MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A N/A N/A N/A CP-OFDM 64QAM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full
Defau 1	Wgap SCC2/CC3 SCC3/CC4 Ilt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC3/CC4 PCC/CC1 SCC1/CC2	190MHz 100MHz r a CA_nX(D-G)_L ag: 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 200MHz 100MHz 200MHz 100MHz 200MHz 100MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full
1 2	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	190MHz 100MHz r a CA_nX(D-G)_L ag: 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 100MHz 200MHz 200MHz 100MHz 200MHz 200MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full
1 2	Wgap SCC2/CC3 SCC3/CC4 Jlt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap	190MHz 100MHz <b>r a CA_nX(D-G)_U</b> ag: 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 100MHz 200MHz 100MHz 100MHz 100MHz 100MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full
1 2	Wgap SCC2/CC3 SCC3/CC4 Ilt Test Settings fo PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC3/CC4 PCC/CC1 SCC1/CC2	190MHz 100MHz r a CA_nX(D-G)_L ag: 100MHz 100MHz 200MHz 200MHz 100MHz 100MHz 100MHz 200MHz 100MHz 200MHz 100MHz 200MHz 100MHz 100MHz	gregated BWchan	nel <800MHz) N/A for this	N/A N/A N/A nfiguration (400MH: DFT-s-OFDM Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	N/A N/A z <= Cumulative Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full Outer_Full

r						
	PCC/CC1	200MHz	Default	N/A for this	DFT-s-OFDM Pi/2 BPSK	Outer_Full
	SCC1/CC2	200MHz	-	test	DFT-s-OFDM	Outer_Full
	0001/002	20010112		1001	Pi/2 BPSK	
1	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz	-		N/A	N/A
	SCC3/CC4	100MHz	-		N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	PCC/CC1	200MHz	-		CP-OFDM	Outer_Full
	100/001	200101112			16QAM	
	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
	3001/002	200101112			16QAM	
2	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A N/A
			-			
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	PCC/CC1	200MHz			CP-OFDM 64QAM	Outer_Full
	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
_					64QAM	
3	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
			-E) III nXO Cor	figuration (400M	Hz <= Cumulative a	
	Derault rest octin		BWchannel <	800MHz)		iggiogatea
	PCC/CC1	100MHz	Default	N/A for this	DFT-s-OFDM	Outer_Full
	100/001	TOOMINE	Delaun		Pi/2 BPSK	
	SCC1/CC2	100MHz		test	DFT-s-OFDM	Outer_Full
	0001/002			1031	Pi/2 BPSK	
1	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz	-		N/A	N/A N/A
			-			
	SCC3/CC4	200MHz			N/A	N/A
	SCC4/CC5	200MHz	-		N/A	N/A
	PCC/CC1	100MHz			CP-OFDM 16QAM	Outer_Full
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
	0001/002				16QAM	
2	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4				N/A	N/A N/A
		200MHz	-			
	SCC4/CC5	200MHz	-		N/A	N/A
	PCC/CC1	100MHz			CP-OFDM 64QAM	Outer_Full
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
•					64QAM	
3	Wgap	90MHz	]		N/A	N/A
	SCC2/CC3	100MHz	1		N/A	N/A
	SCC3/CC4	200MHz	1		N/A	N/A
	SCC4/CC5	200MHz	1		N/A	N/A
Defa			L nXD. CA nX(D	-Q) UL nXD Cor	figuration (400MHz	
			regated BWchan		J	
	PCC/CC1	100MHz	Default	N/A for this	DFT-s-OFDM	Outer_Full
	SCC1/CC2	200MHz		test	Pi/2 BPSK DFT-s-OFDM	Outer_Full
					Pi/2 BPSK	
1	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
	100/001				16QAM	
2	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
_		20010112			16QAM	
	Wgap	90MHz			N/A	N/A
			•	•		

	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
					64QAM	
	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
					64QAM	
3	Wgap	90MHz			N/A	N/A
5	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
Defau	ult Test Settings fo	or a CA_nX(G-I)_U			Cumulative aggregation	ated BWchannel
	PCC/CC1	100MHz	< 800MH Default	z) N/A for this	DFT-s-OFDM	Outer_Full
	FCC/CCT	TOOIVINZ	Delault	IN/A IOI UIIS	Pi/2 BPSK	Outer_Full
	SCC1/CC2	100MHz		test	DFT-s-OFDM	Outer_Full
	0001/002	TOOMITZ		1631	Pi/2 BPSK	Outer_r un
4	W/gop					NI/A
1	Wgap	190MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
	F00/001					Outer_Fuil
	0004/000	(00) (1)			16QAM	0 / E #
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
					16QAM	
2	Wgap	190MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
						N/A
	SCC4/CC5	100MHz			N/A	
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
					64QAM	
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
					64QAM	
3	Wgap	190MHz			N/A	N/A
Ũ	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	<u>N/A</u>
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
Defau					e aggregated BWch	
				N/A for this		
	PCC/CC1	50MHz	Default	IN/A IOI UIIS	DFT-s-OFDM	Outer_Full
	PCC/CC1	SOIVIHZ	Default	IN/A IOI UIIS		Outer_Full
			Default		Pi/2 BPSK	
1	SCC1/CC2	200MHz	Default	test	Pi/2 BPSK DFT-s-OFDM	Outer_Full Outer_Full
1	SCC1/CC2	200MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK	Outer_Full
1	SCC1/CC2 Wgap	200MHz 40MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A	Outer_Full N/A
1	SCC1/CC2 Wgap SCC2/CC3	200MHz 40MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A	Outer_Full N/A N/A
1	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A	Outer_Full N/A N/A N/A
1	SCC1/CC2 Wgap SCC2/CC3	200MHz 40MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A	Outer_Full N/A N/A
1	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM	Outer_Full N/A N/A N/A
1	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	200MHz 40MHz 50MHz 50MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM	Outer_Full N/A N/A N/A Outer_Full
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A N/A CP-OFDM 16QAM CP-OFDM	Outer_Full N/A N/A N/A
1	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2	200MHz 40MHz 50MHz 50MHz 50MHz 200MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM	Outer_Full N/A N/A N/A Outer_Full Outer_Full
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap	200MHz 40MHz 50MHz 50MHz 50MHz 200MHz 40MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A	Outer_Full N/A N/A N/A Outer_Full Outer_Full N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	200MHz 40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A	Outer_Full N/A N/A N/A Outer_Full Outer_Full N/A N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	200MHz 40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz	Default		Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A	Outer_Full N/A N/A N/A Outer_Full Outer_Full N/A N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A CP-OFDM 64QAM	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A
	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz 200MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz			Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A	Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz		test	Pi/2 BPSK DFT-s-OFDM Pi/2 BPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A	Outer_Full N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A

	SCC1/CC2	200MHz	]	test	N/A	N/A
	Wgap	40MHz			N/A	N/A
	SCC2/CC3	50MHz			DFT-s-OFDM	Outer_Full
					Pi/2 BPSK	
	SCC3/CC4	50MHz			DFT-s-OFDM	Outer_Full
					Pi/2 BPSK	
	PCC/CC1	50MHz			N/A	N/A
	SCC1/CC2	200MHz			N/A	N/A
	Wgap	40MHz			N/A	N/A
2	SCC2/CC3	50MHz			CP-OFDM	Outer_Full
					16QAM	
	SCC3/CC4	50MHz			CP-OFDM	Outer_Full
					16QAM	
	PCC/CC1	50MHz			N/A	N/A
	SCC1/CC2	200MHz			N/A	N/A
	Wgap	40MHz			N/A	N/A
3	SCC2/CC3	50MHz			CP-OFDM	Outer_Full
					64QAM	
	SCC3/CC4	50MHz			CP-OFDM	Outer_Full
					64QAM	
		onfiguration of each				
NOTE		SCC/CCj means PCC		carrier CCi and S	CC is on componen	t carrier CCj, with
	CCi or CCj fre	equencies defined in	TS38.508-1 [10].			

# Table 6.2A.2.1.4.1-4: Intra-band Contiguous UL CA Test Configuration Table (Power Class 1, Non-contiguous allocation)

Test Er				onditions			
	nvironment as specif	ied in TS 38.508-1	[10]	Normal			
	use [4.1]						
Test Fr	equencies as specifi	ied in TS 38.508-1	[10]	For intra-band contiguous CA: Mid range.			
subclau	use [4.3.1.2.3] for dif	ferent CA bandwid	th classes	For intra-band non-contiguous CA: Lowest range with			
					phest range with Max W		
	C Combination settin				ated channel bandwid	th of the CA	
	iration) as specified i			configuration			
	5A.2-2 for the CA Co		bandwidth				
	nation sets supported			400 1.1.1-			
Test St	CS as specified in Ta	adie 5.3.5-1	Teet Der	120 kHz			
Test	CC 9 Manufact		Test Para Test	DL RB	UL Modulation	UL RB	
Test ID	CC & Mapping	ChBw(MHz)	frequency	allocation		allocation	
	(NOTE 2)						
	Default T	est Settings for a	CA_nXB, CA	_nXD, CA_XG,	CA_nXO Configuration	on 🛛	
1 -	PCC/CC1	Default	Default	N/A for this	CP-OFDM 64QAM	Outer_1RB_Left	
'	SCC/CC2			test	CP-OFDM 64QAM	Outer_1RB_Right	
	PCC/CC1				DFT-s-OFDM Pi/2 BPSK	[Outer_0.9_Left]	
2 -	SCC/CC2	-			DFT-s-OFDM Pi/2	[Outer_0.9_Right]	
	500/004				BPSK		
	PCC/CC1				DFT-s-OFDM Pi/2	[Outer_0.9_Left]	
3 -	SCC/CC2	-			QPSK DFT-s-OFDM Pi/2	[Outer_0.9_Right]	
Ŭ	300/002				QPSK		
I	Defa	ault Test Settings	for a CA nX	(D-G). CA nX(D	-O) Configuration		
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_1RB_Left	
					QPSK		
	SCC1/CC2			test	DFT-s-OFDM	Outer_1RB_Right	
1					QPSK	-	
L	Wgap				N/A	N/A	
L	SCC2/CC3				N/A	N/A	
	SCC3/CC4				N/A	N/A	
	PCC/CC1				DFT-s-OFDM Pi/2	[Outer_0.9_Left]	
F	0001/000	4			BPSK		
-	SCC1/CC2				DFT-s-OFDM Pi/2	[Outer_0.9_Right]	
2					BPSK	N1/A	
-	Wgap				N/A	N/A	
	SCC2/CC3	-			N/A	N/A	
	SCC3/CC4	-				N/A	
	PCC/CC1				DFT-s-OFDM Pi/2 QPSK	[Outer_0.9_Left]	
	SCC1/CC2				DFT-s-OFDM Pi/2	[Outer_0.9_Right]	
3					QPSK		
L	Wgap				N/A	N/A	
L	SCC2/CC3				N/A	N/A	
	SCC3/CC4				N/A	N/A	
NOTE		figuration of each F					
NOTE 2	2 PCC/CCi and SC	C/CCI means PC	is on compo	onent carrier CCi	and SCC is on compor	nent carrier CCj,	

## Table 6.2A.2.1.4.1-5: Intra-band Contiguous UL CA Test Configuration Table (Power Class 2, 3 and 4, single CC MPR requirement)

			Default Co	onditions				
Test E	Environment as specifi	ed in TS 38.508-1	[10]	Normal				
	ause [4.1]							
	requencies as specifi			Lowest range, H	lighest range			
	ause [4.3.1.2.3] for diff					(		
	CC Combination settin				ated channel bandwidtl	n of the CA		
	juration) as specified in			configuration				
	2-2 for the CA Configu		awiath					
	ination sets supported SCS as specified in Ta			120 kHz				
1651 0	bud as specified in Ta	DIE 5.5.5-1	Test Para	-				
Test	CC & Mapping	ChBw(MHz)	Test	DL RB	UL Modulation	UL RB		
ID		·····/	frequency	allocation	•=•	allocation		
	(NOTE 2)		. ,					
Defa					e aggregated BWcha			
4	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM QPSK	Inner_Full		
1	SCC/CC2	-		toot	QPSN			
	PCC/CC1	-		test	- DFT-s-OFDM	 Outer_Full		
2	FUC/UCT				QPSK	Outer_Full		
2	SCC/CC2	{			-	-		
		s for a CA nXD C	onfiguration	(Cumulative age	gregated BWchannel	<= 400MHz)		
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Inner_Full		
1					QPSK	_		
	SCC/CC2	1		test	-	-		
	PCC/CC1				DFT-s-OFDM	Outer_Full		
2		ļ			QPSK			
	SCC/CC2				-	-		
	1: The specific conf							
NOTE					and SCC is on compon	ent carrier CCj,		
L	with CCI or CCJ fi	requencies defined	a in 1838.508	-1 [10].				

Table 6.2A.2.1.4.1-6: Intra-band Contiguous UL CA Test Configuration Table (Power Class 2, 3 and 4,  $MPR_{C_CA}$ )

			Default Cond	litions		
	Environment as spe	cified in TS 38.508-		Normal		
[4.1]	- requencies as spe	oified in TS 29 E09	1 [10] aubalauaa	For intro bond o	ontiguous CA: Mid ra	222
	.2.3] for different CA				ion-contiguous CA: Mild Ta	
-				Max Wgap, Hig	nest range with Max	Ngap.
	CC Combination set				ated channel bandwid	th of the CA
	juration) as specifie 2-2 for the CA Confi			configuration		
combi	ination sets support	ed by the UE				
Test S	SCS as specified in	Table 5.3.5-1		120 kHz		
Test	CC & Mapping	ChBw(MHz)	Test Param Test	eters DL RB	UL Modulation	UL RB
ID	(NOTE 2)		frequency	allocation		allocation
-		gs for a CA nXB.	NXC UL nXB Co	nfiguration (800	//Hz <= Cumulative :	aggregated
-		-	BWchannel <= 2			aggi ogaloa
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_Full
1	SCC/CC2			test	QPSK DFT-s-OFDM	Outer_Full
					QPSK	
	PCC/CC1				DFT-s-OFDM	Outer_Full
2	SCC/CC2				16QAM DFT-s-OFDM	Outer_Full
					16QAM	
	PCC/CC1				CP-OFDM	Outer_Full
3	SCC/CC2				QPSK CP-OFDM	Outer_Full
	000/002				QPSK	
	PCC/CC1				CP-OFDM	Outer_Full
4	SCC/CC2				16QAM CP-OFDM	Outer_Full
	300/002				16QAM	Outer_Full
	PCC/CC1				CP-OFDM	Outer_Full
5	SCC/CC2				64QAM CP-OFDM	Outor Full
	300/002				64QAM	Outer_Full
Defa					aggregated BWcha	
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_Full
1	SCC/CC2			test	QPSK DFT-s-OFDM	Outer_Full
	000/002			1001	QPSK	
	PCC/CC1				CP-OFDM	Outer_Full
2	SCC/CC2				QPSK CP-OFDM	Outer_Full
	000/002					
					QPSK	
	PCC/CC1				CP-OFDM	Outer_Full
3					CP-OFDM 16QAM	
3	PCC/CC1 SCC/CC2				CP-OFDM 16QAM CP-OFDM	Outer_Full Outer_Full
3					CP-OFDM 16QAM CP-OFDM 16QAM CP-OFDM	
3	SCC/CC2 PCC/CC1				CP-OFDM 16QAM CP-OFDM 16QAM CP-OFDM 64QAM	Outer_Full Outer_Full
	SCC/CC2				CP-OFDM 16QAM CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM	Outer_Full
4	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings for				CP-OFDM 16QAM CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha	Outer_Full Outer_Full Outer_Full
4	SCC/CC2 PCC/CC1 SCC/CC2	or a CA_nXB Conf 200MHz	iguration (400MH	<b>z &lt;= Cumulative</b> N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM 64QAM aggregated BWcha DFT-s-OFDM	Outer_Full Outer_Full Outer_Full
4	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings for PCC/CC1	200MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha DFT-s-OFDM QPSK	Outer_Full Outer_Full Outer_Full nnel < 800MHz) Outer_Full
4 Defa	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings fo PCC/CC1 SCC/CC2				CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM 64QAM aggregated BWcha DFT-s-OFDM	Outer_Full Outer_Full Outer_Full nnel < 800MHz)
4 Defa	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings for PCC/CC1	200MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha DFT-s-OFDM QPSK DFT-s-OFDM QPSK CP-OFDM	Outer_Full Outer_Full Outer_Full nnel < 800MHz) Outer_Full
4 Defa	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings fo PCC/CC1 SCC/CC2 PCC/CC1	200MHz 400MHz 200MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha DFT-s-OFDM QPSK DFT-s-OFDM QPSK CP-OFDM QPSK	Outer_Full Outer_Full Outer_Full <b>nnel &lt; 800MHz)</b> Outer_Full Outer_Full Outer_Full
4 Defa 1	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings fo PCC/CC1 SCC/CC2	200MHz 400MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha DFT-s-OFDM QPSK DFT-s-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK CP-OFDM	Outer_Full Outer_Full Outer_Full nnel < 800MHz) Outer_Full Outer_Full
4 Defa 1	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings fo PCC/CC1 SCC/CC2 PCC/CC1	200MHz 400MHz 200MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM aggregated BWcha DFT-s-OFDM QPSK DFT-s-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK CP-OFDM	Outer_Full Outer_Full Outer_Full nnel < 800MHz) Outer_Full Outer_Full Outer_Full
4 Defa 1	SCC/CC2 PCC/CC1 SCC/CC2 ult Test Settings fo PCC/CC1 SCC/CC2 PCC/CC1 SCC/CC2	200MHz 400MHz 200MHz 400MHz		N/A for this	CP-OFDM 16QAM CP-OFDM 64QAM CP-OFDM 64QAM <b>aggregated BWcha</b> DFT-s-OFDM QPSK DFT-s-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK	Outer_Full Outer_Full Outer_Full nnel < 800MHz) Outer_Full Outer_Full Outer_Full Outer_Full

r			7	1	00.0701/	
	PCC/CC1	200MHz			CP-OFDM 64QAM	Outer_Full
4	SCC/CC2	400MHz			CP-OFDM	Outer_Full
	000/002	40010112			64QAM	
Def	ault Test Settings	for a CA_nXG, CA	nXO Configurati	on (Cumulative a	ggregated BWcha	nnel < 400MHz)
	PCC/CC1	Default	Default	N/A for this	CP-OFDM	Outer_Full
1	000/000				QPSK	
-	SCC/CC2			test	CP-OFDM	Outer_Full
	PCC/CC1				QPSK CP-OFDM	Outer_Full
_	100/001				16QAM	
2	SCC/CC2				CP-OFDM	Outer_Full
					16QAM	
	PCC/CC1				CP-OFDM	Outer_Full
3	000/000				64QAM	Outon Full
	SCC/CC2				CP-OFDM 64QAM	Outer_Full
	Default Test Sett	tings for a CA_nXD	Configuration (C	umulative aggre		< 400MHz)
	PCC/CC1	100MHz	Default	N/A for this	CP-OFDM	Outer_Full
1			-		QPSK	
1	SCC/CC2	200MHz		test	CP-OFDM	Outer_Full
	D00/004	4000411-	-		QPSK	
	PCC/CC1	100MHz			CP-OFDM 16QAM	Outer_Full
2	SCC/CC2	200MHz	-		CP-OFDM	Outer_Full
					16QAM	0 000 0
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
3			-		64QAM	
Ū	SCC/CC2	200MHz			CP-OFDM 64QAM	Outer_Full
Def	fault Test Settings	for a CA_nX(D-G)				
		Configuration (80				
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_Full
					QPSK	
	SCC1/CC2			test	DFT-s-OFDM	Outer_Full
1	Wgap				QPSK N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	PCC/CC1				DFT-s-OFDM	Outer_Full
	0004/000				16QAM	
2	SCC1/CC2				DFT-s-OFDM 16QAM	Outer_Full
2	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
	0004/000				QPSK	
3	SCC1/CC2				CP-OFDM QPSK	Outer_Full
5	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
	0004/000				16QAM	
4	SCC1/CC2				CP-OFDM 16QAM	Outer_Full
4	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
	0004/000				64QAM	0
5	SCC1/CC2				CP-OFDM 64QAM	Outer_Full
			1			
	Wdap					N/A
	Wgap SCC2/CC3				N/A N/A	N/A N/A

-	SCC3/CC4				N/A	N/A
Defa	ault Test Settings	for a CA_nX(D-H)_U (800MHz <= Cumu				Configuration
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_Full
	100,001	Dolaali	Dolaali		QPSK	
	SCC1/CC2			test	DFT-s-OFDM	Outer_Full
					QPSK	0 4101_1 411
1	Wgap	-			N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	PCC/CC1	-			DFT-s-OFDM	Outer_Full
					16QAM	• u.
	SCC1/CC2				DFT-s-OFDM	Outer_Full
					16QAM	• u.
2	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4	-			N/A	N/A
	SCC4/CC5	-			N/A	N/A
	PCC/CC1	-			CP-OFDM	Outer_Full
	100/001				QPSK	Outer_r un
	SCC1/CC2	-			CP-OFDM	Outer_Full
	0001/002				QPSK	
3	Wgap	-			N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC3/CC4 SCC4/CC5	-			N/A N/A	N/A
	PCC/CC1	-			CP-OFDM	
	PUC/UC1					Outer_Full
	0001/000	-			16QAM	Outor Full
	SCC1/CC2				CP-OFDM	Outer_Full
4	14/				16QAM	N1/A
	Wgap				N/A	N/A
	SCC2/CC3	-			N/A	N/A
	SCC3/CC4	-			N/A	N/A
	SCC4/CC5	-			N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
	0004/000				64QAM	
	SCC1/CC2				CP-OFDM	Outer_Full
5		-			64QAM	<b>N</b> 1/A
•	Wgap	-			N/A	N/A
	SCC2/CC3	-			N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
Def	fault Test Settings	s for a CA_nX(D-I)_U				Configuration
	<b>D D D D D D D D D D</b>	(800MHz <= Cumu				
	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM	Outer_Full
		-			QPSK	
	SCC1/CC2			test	DFT-s-OFDM	Outer_Full
		-			QPSK	
1	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5	-			N/A	N/A
	SCC5/CC6				N/A	N/A
	PCC/CC1				DFT-s-OFDM	Outer_Full
	100,001				16QAM	
					DFT-s-OFDM	Outer_Full
	SCC1/CC2	-			16QAM	
2	SCC1/CC2 Wgap				N/A	N/A
2	SCC1/CC2 Wgap SCC2/CC3					N/A
2	SCC1/CC2 Wgap				N/A	
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4				N/A N/A	N/A N/A
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 SCC4/CC5				N/A N/A N/A N/A	N/A N/A N/A
2	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4				N/A N/A N/A	N/A N/A

	SCC1/CC2				CP-OFDM	Outer_Full
					QPSK	
	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	SCC5/CC6				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
	100/001					
					16QAM	
	SCC1/CC2				CP-OFDM	Outer_Full
					16QAM	
4	Wgap				N/A	N/A
-	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	SCC5/CC6				N/A	N/A
	PCC/CC1				CP-OFDM	Outer_Full
					64QAM	0 4101_1 411
	0004/000				CP-OFDM	Outon Full
	SCC1/CC2					Outer_Full
					64QAM	
5	Wgap				N/A	N/A
	SCC2/CC3				N/A	N/A
	SCC3/CC4				N/A	N/A
	SCC4/CC5				N/A	N/A
	SCC5/CC6				N/A	N/A
Defau	ult Test Settings for	or a CA_nX(D-G)_U			figuration (400MH	z <= Cumulative
		agg	regated BWchanr	nel <800MHz)		
	PCC/CC1	200MHz	Default	N/A for this	DFT-s-OFDM	Outer_Full
			20101011		QPSK	0 4101_1 411
	0004/000	0000411	4			
	SCC1/CC2	200MHz		test	DFT-s-OFDM	Outer_Full
1					QPSK	
	Wgap	190MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz	4		N/A	N/A
			-			
	PCC/CC1	200MHz			CP-OFDM	Outer_Full
					QPSK	
	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
2					QPSK	
_	Wgap	190MHz	1		N/A	N/A
	SCC2/CC3	100MHz	4			N/A
			4		N/A	
	SCC3/CC4	100MHz			N/A	N/A
	PCC/CC1	200MHz			CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2	200MHz	4		CP-OFDM	Outer_Full
~	0001/002					
3			-		16QAM	
	Wgap	190MHz	ļ		N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	PCC/CC1	200MHz	1		CP-OFDM	Outer_Full
	100/001					
			{		64QAM	<b>a</b> . –
	SCC1/CC2	200MHz			CP-OFDM	Outer_Full
4					64QAM	
	Wgap	190MHz	]		N/A	N/A
	SCC2/CC3	100MHz	1		N/A	N/A
			4			
	SCC3/CC4	100MHz			N/A	N/A
Defau	ut Test Settings fo	or a CA_nX(D-G)_U			inguration (400MH	z <= Cumulative
			regated BWchanr	1		
	PCC/CC1	100MHz	Default	N/A for this	DFT-s-OFDM	Outer_Full
					QPSK	—
		100MHz		toot	DFT-s-OFDM	Outer_Full
	SCC1/CC2			test		
	SCC1/CC2				QPSK	
1				ļ		
1	Wgap	190MHz			N/A	N/A
1	Wgap	190MHz			N/A	
1	Wgap SCC2/CC3	190MHz 200MHz			N/A N/A	N/A
1	Wgap SCC2/CC3 SCC3/CC4	190MHz 200MHz 200MHz			N/A N/A N/A	N/A N/A
1	Wgap SCC2/CC3	190MHz 200MHz			N/A N/A	N/A

	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
					QPSK	
	Wgap	190MHz			N/A	N/A
	SCC2/CC3	200MHz			N/A	N/A
	SCC3/CC4	200MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM 16QAM	Outer_Full
3	SCC1/CC2	100MHz			CP-OFDM 16QAM	Outer_Full
3	Waap	190MHz			N/A	N/A
-	Wgap SCC2/CC3	200MHz			N/A N/A	N/A
-		200MHz				N/A
	SCC3/CC4				N/A	
-	PCC/CC1	100MHz				Outer_Full
4	SCC1/CC2	100MHz			CP-OFDM 64QAM	Outer_Full
-	Wgap	190MHz			N/A	N/A
	SCC2/CC3	200MHz			N/A	N/A
	SCC3/CC4	200MHz			N/A	N/A
Defau	It Test Settings fo	or a CA_nX(D-H)_UI			nfiguration (400MH	z <= Cumulative
			regated BWchanr			
	PCC/CC1	200MHz	Default	N/A for this	DFT-s-OFDM QPSK	Outer_Full
	SCC1/CC2	200MHz		test	DFT-s-OFDM QPSK	Outer_Full
1	Wgap	90MHz			N/A	N/A
F	SCC2/CC3	100MHz			N/A	N/A
-	SCC3/CC4	100MHz			N/A	N/A
-	SCC4/CC5	100MHz			N/A	N/A
	PCC/CC1	200MHz			CP-OFDM	
					QPSK	Outer_Full
2	SCC1/CC2	200MHz			CP-OFDM QPSK	Outer_Full
2	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	PCC/CC1	200MHz			CP-OFDM 16QAM	Outer_Full
-	SCC1/CC2	200MHz			CP-OFDM 16QAM	Outer_Full
3	Wgap	90MHz			N/A	N/A
-	SCC2/CC3	100MHz			N/A	N/A
-	SCC3/CC4	100MHz			N/A	N/A
-	SCC4/CC5	100MHz			N/A N/A	N/A
	PCC/CC1				CP-OFDM	
		200MHz			16QAM	Outer_Full
4	SCC1/CC2	200MHz			CP-OFDM 16QAM	Outer_Full
-	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
Γ	SCC4/CC5	100MHz			N/A	N/A
[		ngs for a CA_nX(O⋅			Hz <= Cumulative a	ggregated
-			BWchannel < 8		'	
		100MHz	Default	N/A for this	DFT-s-OFDM	Outer_Full
	PCC/CC1				QPSK	
	PCC/CC1 SCC1/CC2	100MHz		test	DFT-s-OFDM QPSK	Outer_Full
1	SCC1/CC2			test	DFT-s-OFDM	Outer_Full
1 -	SCC1/CC2 Wgap	100MHz 90MHz		test	DFT-s-OFDM QPSK N/A	N/A
1 -	SCC1/CC2 Wgap SCC2/CC3	100MHz 90MHz 100MHz		test	DFT-s-OFDM QPSK N/A N/A	N/A N/A
1 -	SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	100MHz 90MHz 100MHz 200MHz		test	DFT-s-OFDM QPSK N/A N/A N/A	N/A N/A N/A
1 -	SCC1/CC2 Wgap SCC2/CC3	100MHz 90MHz 100MHz		test	DFT-s-OFDM QPSK N/A N/A	N/A N/A

	Wgap	90MHz	]		N/A	N/A
	SCC2/CC3	100MHz	1		N/A	N/A
	SCC3/CC4	200MHz			N/A	N/A
	SCC4/CC5	200MHz			N/A	N/A
	PCC/CC1	100MHz	-		CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2	100MHz			CP-OFDM 16QAM	Outer_Full
3	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	200MHz			N/A	N/A
	SCC4/CC5	200MHz	-		N/A	N/A
	PCC/CC1	100MHz	-		CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2	100MHz			CP-OFDM 16QAM	Outer_Full
4	Wgap	90MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	200MHz			N/A	N/A
	SCC4/CC5	200MHz	-		N/A	N/A
Defa			L nXD. CA nX(D	-Q) UL nXD Cor	figuration (400MHz	
	J	agg	regated BWchan	nel < 800MHz)	•	
	PCC/CC1	100MHz	Default	N/A for this	DFT-s-OFDM QPSK	Outer_Full
	SCC1/CC2	200MHz		test	DFT-s-OFDM QPSK	Outer_Full
1	Wgap	90MHz			N/A	N/A
•	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM QPSK	Outer_Full
	SCC1/CC2	200MHz			CP-OFDM QPSK	Outer_Full
2	Wgap	90MHz			N/A	N/A
_	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM 16QAM	Outer_Full
	SCC1/CC2	200MHz			CP-OFDM 16QAM	Outer_Full
3	Wgap	90MHz			N/A	N/A
5	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC3/CC4 SCC4/CC5	100MHz			N/A N/A	N/A N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM 16QAM	Outer_Full
	SCC1/CC2	200MHz			CP-OFDM 16QAM	Outer_Full
4	Wgap	90MHz			N/A	N/A
-	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A N/A	N/A
	SCC5/CC6	100MHz			N/A N/A	N/A
Defau			nXG Configurat	tion (400MHz <= 0	Cumulative aggrega	
-	-		< 800MH	z)		
	PCC/CC1	100MHz	Default	N/A for this	DFT-s-OFDM QPSK	Outer_Full
	SCC1/CC2	100MHz		test	DFT-s-OFDM	Outer_Full
1					QPSK I	
1	Wgap	190MHz			QPSK N/A	N/A

	0000/004	1001411-	1	1	N1/A	N1/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM QPSK	Outer_Full
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
	0001/002	TOOIVITIZ			QPSK	
2	Wgap	190MHz			N/A	N/A
-	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
					16QAM	
3	Wgap	190MHz			N/A	N/A
	SCC2/CC3	100MHz			N/A	N/A
	SCC3/CC4	100MHz			N/A	N/A
	SCC4/CC5	100MHz			N/A	N/A
	SCC5/CC6	100MHz			N/A	N/A
	PCC/CC1	100MHz			CP-OFDM	Outer_Full
					16QAM	
	SCC1/CC2	100MHz			CP-OFDM	Outer_Full
	14/2020	4000411-			16QAM N/A	N/A
4	Wgap SCC2/CC3	190MHz 100MHz			N/A N/A	N/A N/A
	SCC3/CC4	100MHz			N/A N/A	N/A N/A
	SCC4/CC5	100MHz			N/A N/A	N/A N/A
	SCC5/CC6	100MHz			N/A	N/A
Defa		or a CA_nX(D-O)_U	I nXD Configura	tion (Cumulative		
20.4	PCC/CC1	50MHz	Default	N/A for this	CP-OFDM	Outer_Full
	100,001	0011112	Donaut		QPSK	
	SCC1/CC2	200MHz		test		
				lesi		Outer Full
1	0001/002	200101112		iesi	CP-OFDM QPSK	Outer_Full
1		40MHz		lesi		Outer_Full N/A
1	Wgap SCC2/CC3			lesi	QPSK N/A N/A	N/A N/A
1	Wgap SCC2/CC3 SCC3/CC4	40MHz		lesi	QPSK N/A N/A N/A	N/A N/A N/A
1	Wgap SCC2/CC3	40MHz 50MHz		lesi	QPSK N/A N/A N/A CP-OFDM	N/A N/A
1	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	40MHz 50MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM	N/A N/A N/A Outer_Full
	Wgap SCC2/CC3 SCC3/CC4	40MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM	N/A N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2	40MHz 50MHz 50MHz 50MHz 200MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM	N/A N/A N/A Outer_Full Outer_Full
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap	40MHz 50MHz 50MHz 50MHz 200MHz 40MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A	N/A N/A N/A Outer_Full Outer_Full N/A
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM	N/A N/A N/A Outer_Full Outer_Full N/A N/A
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM	N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full
	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	40MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM	N/A N/A N/A Outer_Full Outer_Full N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2	40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM	N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz 200MHz		lesi	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	N/A N/A N/A Outer_Full Outer_Full N/A N/A N/A Outer_Full Outer_Full
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz			QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ult Test Settings f	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 50MHz	L_nXO Configura	ation (Cumulative	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 Ult Test Settings for	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz	L_nXO Configura		QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 Ult Test Settings fr PCC/CC1 SCC1/CC2	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 200MHz		ation (Cumulative	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A
2 3 Defat	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ult Test Settings f PCC/CC1 SCC1/CC2 Wgap	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 40MHz 40MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A
2	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 Ult Test Settings fr PCC/CC1 SCC1/CC2	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 200MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A N/A CP-OFDM	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A
2 3 Defat	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ult Test Settings f PCC/CC1 SCC1/CC2 Wgap SCC2/CC3	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 40MHz 50MHz 50MHz 50MHz 50MHz 50MHz 200MHz 40MHz 50MHz 200MHz 200MHz 50MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A
2 3 Defat	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 ult Test Settings f PCC/CC1 SCC1/CC2 Wgap	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 40MHz 40MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A CP-OFDM QPSK CP-OFDM	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A
2 3 Defat	Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         SCC3/CC3         SCC3/CC4         Ut Test Settings f         PCC/CC1         SCC1/CC2         Wgap         SCC3/CC4         SCC1/CC2         Wgap         SCC2/CC3         SCC2/CC3         SCC3/CC4	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM CP-OFDM QPSK	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A
2 3 Defat	Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         SCC3/CC3         SCC3/CC4         Wgap         SCC3/CC4         Wgap         SCC3/CC4         Wgap         SCC3/CC4         Wgap         SCC1/CC2         Wgap         SCC2/CC3         SCC2/CC3         SCC2/CC4         PCC/CC1         SCC3/CC4         PCC/CC1	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full
2 3 Defat	Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         Ult Test Settings f         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A CP-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full
2 3 Defat	Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 Ult Test Settings f PCC/CC1 SCC1/CC2 Wgap SCC2/CC3 SCC3/CC4 PCC/CC1 SCC3/CC4 PCC/CC1 SCC3/CC4	40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 40MHz 50MHz 50MHz 40MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full N/A N/A N/A
2 3 Defat	Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4         Ult Test Settings f         PCC/CC1         SCC1/CC2         Wgap         SCC2/CC3         SCC1/CC2         Wgap         SCC2/CC3         SCC3/CC4         PCC/CC1         SCC3/CC4         PCC/CC1         SCC3/CC4	40MHz 50MHz 50MHz 200MHz 200MHz 40MHz 50MHz 50MHz 200MHz 200MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz 50MHz		<b>ition (Cumulative</b> N/A for this	QPSK N/A N/A CP-OFDM 16QAM CP-OFDM 16QAM N/A N/A CP-OFDM 64QAM CP-OFDM 64QAM CP-OFDM 64QAM N/A N/A N/A N/A N/A CP-OFDM QPSK CP-OFDM QPSK CP-OFDM QPSK N/A N/A	N/A N/A N/A Outer_Full Outer_Full N/A N/A Outer_Full Outer_Full N/A N/A N/A N/A N/A N/A Outer_Full Outer_Full Outer_Full Outer_Full Outer_Full

	SCC3/CC4	50MHz		CP-OFDM	Outer_Full
				16QAM	
	PCC/CC1	50MHz		N/A	N/A
	SCC1/CC2	200MHz		N/A	N/A
	Wgap	40MHz		N/A	N/A
3	SCC2/CC3	50MHz		CP-OFDM	Outer_Full
				64QAM	
	SCC3/CC4	50MHz		CP-OFDM	Outer_Full
				64QAM	
NOTE	1: The specific c	onfiguration of each	RB allocation is defined in Table 6.1	-1.	
NOTE	2: PCC/CCi and	SCC/CCj means PC	C is on component carrier CCi and	SCC is on compone	ent carrier CCj,
	with CCi or CO	Cj frequencies define	d in TS38.508-1 [10].		•

### Table 6.2A.2.1.4.1-7: Intra-band Contiguous UL CA Test Configuration Table (Power Class 2, 3 and 4, Non-contiguous allocation)

			Default (	Conditions				
	Environment as specifi ause [4.1]	ied in TS 38.508-1	[10]	Normal				
Test F	requencies as specifi	ed in TS 38.508-1	[10]	Mid range				
subcla	ause [4.3.1.2.3] for diff	ferent CA bandwid	lth classes	-				
	CC Combination settin				ated channel bandwidt	th of the CA		
	uration) as specified i			configuration				
	.5A.2-2 for the CA Co		bandwidth					
	nation sets supported			400.111				
Test S	SCS as specified in Ta	able 5.3.5-1	Test Des	120 kHz				
Test	CC 9 Manufact		Test Par Test	DL RB	UL Modulation	UL RB		
ID	CC & Mapping	ChBw(MHz)	frequency	allocation		allocation		
	(NOTE 2)		nequency	anocation		anocation		
Def	ault Test Settings fo	r a CA_XG, CA_n	XO Configur	ration (Cumulative aggregated BWchannel < 400MHz)				
1	PCC/CC1	Default	Default	N/A for this	DFT-s-OFDM QPSK	Outer_1RB_Left		
1	SCC/CC2			test	DFT-s-OFDM QPSK	Outer_1RB_Right		
_	PCC/CC1				DFT-s-OFDM Pi/2 BPSK	[Outer_0.9_Left]		
2	SCC/CC2	-			DFT-s-OFDM Pi/2 BPSK	[Outer_0.9_Right]		
	PCC/CC1	•			DFT-s-OFDM Pi/2 QPSK	[Outer_0.9_Left]		
3	SCC/CC2				DFT-s-OFDM Pi/2 QPSK	[Outer_0.9_Right]		
NOTE NOTE			C is on compo	onent carrier CCi	e 6.1-1. and SCC is on compo	nent carrier CCj,		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.2A.2.1.4.1-1 to Table 6.2A.2.1.4.1-7.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.2.1.4.3.

#### 6.2A.2.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels
- 2. The SS shall configure SCC as per TS 38.508-1 [10] subclause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in subclause 6.2A.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.2A.2.1.4.1-1 to Table 6.2A.2.1.4.1-7. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec starting from the first TPC command in this step to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 8. Measure UE EIRP in the Tx beam peak direction in the accumulative aggregated channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in 6.2A.2.1.5. EIRP test procedure is defined in Annex K.1.3. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 2: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.2A.2.1.4.1-1 to Table 6.2A.2.1.4.1-7, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.2A.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6. In test procedure step 1, for SCC configuration there are no additional message contents.

#### 6.2A.2.1.5 Test requirement

The EIRP derived in step 8 shall be within the range prescribed by the nominal maximum output power and tolerance in the applicable table from Table 6.2A.2.1.5-1 to Table 6.2A.2.1.5-17.

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
1	n257, n258, n261	40.0	14.4	[7.0]	[18.6]-TT	55
1	n260	38.0	14.4	[7.0]	[16.6]-TT	55
2	n257, n258, n261	40.0	14.4	[7.0]	[18.6]-TT	55
2	n260	38.0	14.4	[7.0]	[16.6]-TT	55
3	n257, n258, n261	40.0	10	[5]	[25.0]-TT	55
3	n260	38.0	10	[5]	[23.0]-TT	55
4	n257, n258, n261	40.0	10	[5]	[25.0]-TT	55
4	n260	38.0	10	[5]	[23.0]-TT	55
NOTE 1	: TT for each band a	nd accumulative aggre	egated band	width is specifie	ed in Table 6.2A.2.1.	5-5.

Table 6.2A.2.1.5-1: MPR requirements for Intra-band Contiguo	ous III CA (Power Class 1 MPR)
Table 0.2A.2.1.3-1. WIF IN requirements for initia-band Contiguo	JUS OL CA (FOWEI GIASS I, WIFINarrow)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)		
Test	Test requirements for a CA_nXG, CA_nXO Configuration (Cumulative aggregated BWchanne							
1	n257, n258, n261	40.0	5.5	[5.0]	[29.5]-TT	55		
1	n260	38.0	5.5	[5.0]	[27.5]-TT	55		
2	n257, n258, n261	40.0	3.0	[2.0]	[35.0]-TT	55		
2	n260	38.0	3.0	[2.0]	[33.0]-TT	55		
•	Test requirements fo	r a CA_nXD Configur	ation (Cum	ulative aggreg	ated BWchannel <	= 400MHz)		
1	n257, n258, n261	40.0	5.5	[5.0]	[29.5]-TT	55		
1	n260	38.0	5.5	[5.0]	[27.5]-TT	55		
2	n257, n258, n261	40.0	3.0	[2.0]	[35.0]-TT	55		
2	n260	38.0	3.0	[2.0]	[33.0]-TT	55		
3	n257, n258, n261	40.0	3.5	[3.0]	[33.5]-TT	55		
3	n260	38.0	3.5	[3.0]	[31.5]-TT	55		
NOTE 1	: TT for each band a	nd accumulative aggre	gated band	vidth is specifie	d in Table 6.2A.2.1.	5-5.		

# Table 6.2A.2.1.5-2: MPR requirements for Intra-band Contiguous UL CA (Power Class 1, single CC MPR requirement)

Table 6.2A.2.1.5-3: MPR requirements for Intra-band Contiguous UL CA (Power Class 1, MPR<sub>C\_CA</sub>)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
Tes	st requirements for a CA_nXB, CA_	nXC_UL_nXB Configuration (80 BWchannel <= 1400MHz)	0MHz <= C	umulative	aggrega	ted
1	n257, n258, n261	40.0	[8.2]	[5.0]	[26.8]- TT	55
1	n260	38.0	[8.2]	[5.0]	[24.8]- TT	55
2	n257, n258, n261	40.0	[9.7]	[5.0]	[25.3]- TT	55
2	n260	38.0	[9.7]	[5.0]	[23.3]- TT	55
3	n257, n258, n261	40.0	[9.2]	[5.0]	[25.8]- TT	55
3	n260	38.0	[9.2]	[5.0]	[23.8]- TT	55
4	n257, n258, n261	40.0	[8.7]	[5.0]	[26.3]- TT	55
4	n260	38.0	[8.7]	[5.0]	[24.3]-	55
5	n257, n258, n261	40.0	[11.2]	[7.0]	TT [21.8]- TT	55
5	n260	38.0	[11.2]	[7.0]	[19.8]- TT	55
Test	ا requirements for a CA_nXD, CA_n	B Configuration (400MHz <= Cu 800MHz)	mulative a	ggregated		nnel <
1	n257, n258, n261	40.0	7.7	[5.0]	[27.3]- TT	55
1	n260	38.0	7.7	[5.0]	[25.3]- TT	55
2	n257, n258, n261	40.0	8.7	[5.0]	[26.3]- TT	55
2	n260	38.0	8.7	[5.0]	[24.3]- TT	55
3	n257, n258, n261	40.0	10.7	[7.0]	[22.3]- TT	55
3	n260	38.0	10.7	[7.0]	[20.3]- TT	55
Test	requirements for a CA_nXG, CA_n	XO, CA_nXD Configuration (Cur 400MHz)	nulative ag	gregated		nel <
1	n257, n258, n261	40.0	5.5	[5.0]	[29.5]- TT	55
1	n260	38.0	5.5	[5.0]	[27.5]- TT	55
2	n257, n258, n261	40.0	6.5	[5.0]	[28.5]- TT	55
2	n260	38.0	6.5	[5.0]	[26.5]- TT	55
3	n257, n258, n261	40.0	9.0	[5.0]	[26.0]-	55
3	n260	38.0	9.0	[5.0]	TT [24.0]- TT	55
Tes O)	n260 st requirements for a CA_nX(D-G)_ _UL_nXO, CA_nX(D-H)_UL_nXD, C/ {(D-Q)_UL_nXD, CA_nX(G-I)_UL_n/	UL_nXD, CA_nX(D-G)_UL_nXG, A_nX(D-P)_UL_nXD, CA_nX(E-O) (G Configuration (800MHz <= Cu	CA_nX(D-0) UL_nXO,	D)_UL_nX , CA_nX(D	[24.0]- TT D, CA_nX -I)_UL_n	((D- XD,
Tes O)	st requirements for a CA_nX(D-G)_ UL_nXO, CA_nX(D-H)_UL_nXD, C/	UL_nXD, CA_nX(D-G)_UL_nXG, A_nX(D-P)_UL_nXD, CA_nX(E-O)	CA_nX(D-0) UL_nXO,	D)_UL_nX , CA_nX(D	[24.0]- TT D, CA_nX I)_UL_n d BWchai [26.8]	((D- XD,
Tes O)_ CA_nX	st requirements for a CA_nX(D-G)_ _UL_nXO, CA_nX(D-H)_UL_nXD, C/ X(D-Q)_UL_nXD, CA_nX(G-I)_UL_n/	UL_nXD, CA_nX(D-G)_UL_nXG, A_nX(D-P)_UL_nXD, CA_nX(E-O) (G Configuration (800MHz <= Cu 1400MHz)	CA_nX(D-0) )_UL_nXO, mulative a	D)_UL_nX , CA_nX(D lggregated	[24.0]- TT D, CA_n) -I)_UL_n d BWchai [26.8] _TT [24.8]	(D- XD, nnel <=
Tes O)_ CA_nX	st requirements for a CA_nX(D-G)_ _UL_nXO, CA_nX(D-H)_UL_nXD, C/ ((D-Q)_UL_nXD, CA_nX(G-I)_UL_n) n257, n258, n261	UL_nXD, CA_nX(D-G)_UL_nXG, A_nX(D-P)_UL_nXD, CA_nX(E-O) (G Configuration (800MHz <= Cu 1400MHz) 40.0	CA_nX(D-C) )_UL_nXO, mulative a [8.2]	D)_UL_nX D)_UL_nX (D ggregated [5.0]	[24.0]- TT D, CA_nX -I)_UL_n BWchai [26.8] -TT [24.8] -TT [25.3]	( <b>D-</b> XD, nnel <=
Tes O)_ CA_nX 1 1	st requirements for a CA_nX(D-G)_ _UL_nXO, CA_nX(D-H)_UL_nXD, C/ ((D-Q)_UL_nXD, CA_nX(G-I)_UL_n) n257, n258, n261 n260	UL_nXD, CA_nX(D-G)_UL_nXG, A_nX(D-P)_UL_nXD, CA_nX(E-O) (G Configuration (800MHz <= Cu 1400MHz) 40.0 38.0	CA_nX(D-C)_UL_nXO, mulative a [8.2]	D)_UL_nX , CA_nX(D , ggregated [5.0]	[24.0]- TT <b>D, CA_n</b> <b>i)_UL_n</b> <b>BWchai</b> [26.8] _TT [24.8] _TT	( <b>D-</b> XD, nnel <= 55 55

	55
4         n257, n258, n261         40.0         [8.7]         [5.0]         [26.3]         5	55
4 n260 38.0 [8.7] [5.0] [24.3] 5 -TT	55
5         n257, n258, n261         40.0         [11.2]         [7.0]         [21.8]         4	55
	55
Test requirements for a CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-	
O)_UL_nXO, CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(O-E)_UL_nXO, CA_nX(D-I)_UL_nXD,	
CA_nX(D-Q)_UL_nXD, CA_nX(G-I)_UL_nXG Configuration (400MHz <= Cumulative aggregated BWchann	<b>a</b> l
<800MHz)	CI
	55
	55
2 n257, n258, n261 40.0 8.7 [5.0] [26.3]- 5	55
	55
	55
	55
Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative aggregat	ed
BWchannel <400MHz)	
1 n257, n258, n261 40.0 5.5 [5.0] [29.5]- 5 TT	55
1 n260 38.0 5.5 [5.0] [27.5]- 5	55
2 n257, n258, n261 40.0 6.5 [5.0] [28.5]- 5	55
2 n260 38.0 6.5 [5.0] [26.5]- 5	55
	55
3         n260         38.0         9.0         [5.0]         [24.0]-         5           TT         5	55
NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-5.	

# Table 6.2A.2.1.5-4: MPR requirements for Intra-band Contiguous UL CA (Power Class 1, Non-contiguous allocation)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
	Test require	ments for a CA_nX				
1	n257, n258, n261	40.0	[14.4]	[7.0]	[18.6] –TT	55
1	n260	38.0	[14.4]	[7.0]	[16.6] –TT	55
2	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
2	n260	FFS	FFS	FFS	FFS	FFS
3	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
3	n260	FFS	FFS	FFS	FFS	FFS
	Test re	equirements for a C	A_nX(D-G),	CA_nX(D-O) C	Configuration	
1	n257, n258, n261	40.0	[14.4]	[7.0]	[18.6] –TT	55
1	n260	38.0	[14.4]	[7.0]	[16.6] –TT	55
2	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
2	n260	FFS	FFS	FFS	FFS	FFS
3	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
3	n260	FFS	FFS	FFS	FFS	FFS
NOTE 1	: TT for each band and	d accumulative aggre	gated band	width is specifie	d in Table 6.2A.2.1.	5-5.

### Table 6.2A.2.1.5-5: Test Tolerance (MPR for CA for Power class 1)

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## Table 6.2A.2.1.5-6: MPR requirements for Intra-band Contiguous UL CA (Power Class 2, single CC MPR requirement)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)		
Test I	requirements for a C	A_nXG, CA_nXO Cor	figuration	Cumulative ag	gregated BWchan	nel <= 200MHz)		
1	n257, n258, n261	29	0	0	29.0-TT	43		
2	n257, n258, n261	29	2	[1.5]	[25.5]-TT	43		
	Test requirements fo	or a CA_nXD Configur	ation (Cum	ulative aggreg	ated BWchannel <	= 400MHz)		
1	n257, n258, n261	29	0	0	29.0-TT	43		
2	n257, n258, n261	29	3	[2.0]	[24.0]-TT	43		
NOTE 1	NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-9.							

Table 6.2A.2.1.5-7: MPR requirements for Intra-band Contiguous UL CA (Power Class 2, MPR<sub>C\_CA</sub>)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
Test req	uirements for a CA_nXB, nXC_L	UL_nXB Configuration (800MHz <= <= 1400MHz)	Cumulativ	ve aggrega	ated BWc	hannel
1	n257, n258, n261	29	[8.2]	[5.0]	[15.8]- TT	43
2	n257, n258, n261	29	[9.3]	[5.0]	[14.7]- TT	43
3	n257, n258, n261	29	[8.0]	[5.0]	[16.0]- TT	43
4	n257, n258, n261	29	[9.2]	[5.0]	[14.8]- TT	43
5	n257, n258, n261	29	[11.2]	[7.0]	[10.8]- TT	43
Test re	equirements for a CA_nXD, CA_i	nXB Configuration (400MHz <= Cu 800MHz)	mulative a	ggregated	BWchar	nnel <
1	n257, n258, n261	29	7.7	[5.0]	[16.3]- TT	43
2	n257, n258, n261	29	7.5	[5.0]	[16.5]- TT	43
3	n257, n258, n261	29	8.7	[5.0]	[15.3]- TT	43
4	n257, n258, n261	29	10.7	[7.0]	[11.3]- TT	43
Test r	requirements for a CA_nXG, CA_	nXO, CA_nXD Configuration (Cun 400MHz)	nulative ag	gregated	BWchan	nel <
1	n257, n258, n261	29	5	[4.0]	[20.0]- TT	43
2	n257, n258, n261	29	6.5	[5.0]	[17.5]- TT	43
3 Test	n257, n258, n261 requirements for a CA_nX(D-G)	29 )_UL_nXD, CA_nX(D-G)_UL_nXG,	9 CA_nX(D-	[5.0] <b>O)_UL_nX</b>	[15.0]- TT	43 <b>X(D-</b>
Test O)_U CA_nX(	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, ( D-Q)_UL_nXD, CA_nX(G-I)_UL_r		CA_nX(D- )_UL_nXO,	O)_UL_nX , CA_nX(D	[15.0]- TT (D, CA_n) -I)_UL_n I BWchai	X(D- XD,
Test O)_U CA_nX(	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, ( D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261	 )_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-P)_UL_nXD, CA_nX(E-O) זXG Configuration (800MHz <= Cu	CA_nX(D- )_UL_nXO,	O)_UL_nX , CA_nX(D	[15.0]- TT (D, CA_n) -I)_UL_n I BWchai [15.8]- TT	X(D- XD,
Test O)_U CA_nX(	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, ( D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261	)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-P)_UL_nXD, CA_nX(E-O) nXG Configuration (800MHz <= Cu 1400MHz)	CA_nX(D- )_UL_nXO, mulative a	O)_UL_nX , CA_nX(D ggregated	[15.0]- TT ( <b>D, CA_n</b> ) <b>-I)_UL_n</b> <b>BWcha</b> [15.8]- TT [14.7]- TT	X(D- XD, nnel <=
Test           O)_l           CA_nX(           1           2           3	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, ( D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261	29 	CA_nX(D- )_UL_nXO, mulative a	O)_UL_nX , CA_nX(D ggregated [5.0]	[15.0]- TT <b>(D, CA_n)</b> <b>(I)_UL_n</b> <b>BWchai</b> [15.8]- TT [14.7]- TT [16.0]- TT	X(D- XD, nnel <= 43
Test           O)_L           CA_nX(           1           2           3           4	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261	29	CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3]	O)_UL_nX , CA_nX(D ggregated [5.0]	[15.0]- TT <b>(D, CA_n)</b> <b>(D, CA_n)</b> <b>(I)_UL_n</b> <b>(I5.8]-</b> TT [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT	X(D- XD, nnel <= 43 43
Test       O)_I       CA_nX(       1       2       3       4       5	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2]	O)_UL_nX ,CA_nX(D ggregated [5.0] [5.0] [5.0] [5.0] [5.0]	[15.0]- TT <b>(D, CA_n)</b> <b>(D, CA_n)</b> <b>(I)_UL_n</b> <b>(I5.8]-</b> TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT	X(D- XD, nnel <= 43 43 43 43 43 43
Test       O)_L       CA_nX(       1       2       3       4       5       Test       0)_L	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 srequirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G	29 29 29 29 29	CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO	O)_UL_nX O)_UL_nX CA_nX(D ggregated [5.0] [5.0] [5.0] [5.0] [5.0] [7.0] G)_UL_nX(D	[15.0]- TT <b>D, CA_n</b> <b>D, CA_n</b> <b>I BWchau</b> [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT <b>G, CA_n</b> <b>J</b>	X(D- XD, nnel <= 43 43 43 43 43 43 43 (D- XD,
Test       O)_L       CA_nX(       1       2       3       4       5       Test       0)_L	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 srequirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO	O)_UL_nX O)_UL_nX CA_nX(D ggregated [5.0] [5.0] [5.0] [5.0] [5.0] [7.0] G)_UL_nX(D	[15.0]- TT <b>D, CA_n</b> <b>D, CA_n</b> <b>I BWchau</b> [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT <b>G, CA_n</b> <b>J</b>	X(D- XD, nnel <= 43 43 43 43 43 43 43 (D- XD,
Test       O)_U       CA_nX(       1       2       3       4       5       O)_U       CA_nX	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 srequirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO, umulative a	O)_UL_nX , CA_nX(D loggregated [5.0] [5.0] [5.0] [5.0] [5.0] [7.0] 3)_UL_nX(D aggregate	[15.0]- TT D, CA_n. J BWchau [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT G, CA_n2 d BWchau [16.3]-	X(D- XD, nnel <= 43 43 43 43 43 43 (D- XD, nnel <
Test       O)_U       CA_nX(       1       2       3       4       5       O)_U       CA_nX       1	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_ n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO, umulative a	O)_UL_nX , CA_nX(D loggregated [5.0] [5.0] [5.0] [5.0] [7.0] G)_UL_nX(D aggregate [5.0]	[15.0]- TT D, CA_ni J BWchau [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT G, CA_n) d BWchau [16.3]- TT [16.5]-	X(D- XD, nnel <= 43 43 43 43 43 43 43 43 43 43 43 43 43
Test       O)_U       CA_nX(       1       2       3       4       5       O)_U       CA_nX       1       2       3       4       5       CA_nX       1       2       1       2	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_ n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO, umulative a 7.7 7.5	O)_UL_nX CA_nX(D loggregated [5.0] [5.0] [5.0] [5.0] [7.0] G)_UL_nX(D aggregate [5.0] [5.0] [5.0]	[15.0]- TT D, CA_ni. J BWchau [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT [10.8]- TT [10.8]- TT [16.3]- TT [16.5]- TT [15.3]-	X(D- XD, nnel <= 43 43 43 43 43 43 43 43 43 43 43 43
Test       O)_U       CA_nX(       1       2       3       4       5       O)_U       CA_nX       1       2       3       4       5       CA_nX       1       2       3       4       3       4	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_ n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C) JUL_nXO, Junulative a 7.7 7.5 8.7 10.7	O)_UL_nX CA_nX(D ggregated [5.0] [5.0] [5.0] [7.0] 3)_UL_nX(D aggregate [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0]	[15.0]- TT D, CA_n. J BWchau [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT [10.8]- TT [10.8]- TT [16.5]- TT [15.3]- TT [11.3]- TT	X(D- XD, nnel <= 43 43 43 43 43 43 43 43 43 43 43 43 43
Test       O)_U       CA_nX(       1       2       3       4       5       O)_U       CA_nX       1       2       3       4       5       CA_nX       1       2       3       4       3       4	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_ n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C) JUL_nXO, Junulative a 7.7 7.5 8.7 10.7	O)_UL_nX CA_nX(D ggregated [5.0] [5.0] [5.0] [7.0] 3)_UL_nX(D aggregate [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0] [5.0]	[15.0]- TT D, CA_ni J BWchai [15.8]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT [10.8]- TT [10.8]- TT [16.3]- TT [15.3]- TT [11.3]- TT [11.3]- TT [11.3]- TT [16.3]-	X(D- XD, nnel <= 43 43 43 43 43 43 43 43 43 43 43 43 43
Test       O)_L       CA_nX(       1       2       3       4       5       CA_nX       1       2       3       4       5       CA_nX       1       2       3       4       5       7       1       2       3       4       5       7	requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G D-Q)_UL_nXD, CA_nX(G-I)_UL_n n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 requirements for a CA_nX(D-G) JL_nXO, CA_nX(D-H)_UL_nXD, G (D-Q)_UL_nXD, CA_nX(G-I)_UL_ n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261 n257, n258, n261		CA_nX(D- )_UL_nXO, mulative a [8.2] [9.3] [8.0] [9.2] [11.2] CA_nX(D-C )_UL_nXO, umulative a 7.7 7.5 8.7 10.7 nfiguration	O)_UL_nX CA_nX(D aggregated [5.0] [5.0] [5.0] [7.0] G)_UL_nX(D aggregate [5.0]	[15.0]- TT D, CA_ni J BWchai [15.8]- TT [14.7]- TT [14.7]- TT [16.0]- TT [14.8]- TT [10.8]- TT [10.8]- TT [10.8]- TT [16.5]- TT [15.3]- TT [11.3]- TT [11.3]- TT [11.3]- TT	X(D- XD, nnel <= 43 43 43 43 43 43 43 43 43 43 43 43 43

NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-9.

#### Table 6.2A.2.1.5-8: MPR requirements for Intra-band Contiguous UL CA (Power Class 2, Noncontiguous allocation)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)	
	Test require	ments for a CA_nX	B, CA_nXD,	, CA_XG, CA_I	nXO Configuration		
1	n257, n258, n261	29	7	[5.0]	[17.0] –TT	43	
2	n257, n258, n261	FFS	FFS	FFS	FFS	FFS	
3	n257, n258, n261	FFS	FFS	FFS	FFS	FFS	
NOTE 1	NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-9.						

### Table 6.2A.2.1.5-9: Test Tolerance (MPR for CA for Power class 2)

FFS

### Table 6.2A.2.1.5-10: MPR requirements for Intra-band Contiguous UL CA (Power Class 3, single CC MPR requirement)

Test	Band	Min peak EIRP	MPR	T(MPR)	Lower limit	Upper limit
ID		(dBm)	(dB)	(dB)	(dBm)	(dBm)
Test r	requirements for a C	A_nXG, CA_nXO Cor	figuration (	Cumulative ag	gregated BWchan	nel <= 200MHz)
1	n257, n258, n261	22.4	0	0	22.4-TT	43
1	n260	20.6	0	0	20.6-TT	43
2	n257, n258, n261	22.4	2	[1.5]	[18.9]-TT	43
2	n260	20.6	2	[1.5]	[17.1]-TT	43
	Fest requirements fo	r a CA_nXD Configur	ation (Cum	ulative aggreg	ated BWchannel <	= 400MHz)
1	n257, n258, n261	22.4	0	0	22.4-TT	43
1	n260	20.6	0	0	20.6-TT	43
2	n257, n258, n261	22.4	3	[2.0]	[17.4]-TT	43
2	n260	20.6	3	[2.0]	[15.6]-TT	43
NOTE 1	: TT for each band a	nd accumulative aggre	gated bandy	width is specifie	d in Table 6.2A.2.1.	5-13.

Table 6.2A.2.1.5-11: MPR requirements for Intra-band Contiguous UL CA (Power Class 3, MPR<sub>C\_CA</sub>)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
Те	est requirements for a CA_nXB, nX0	C_UL_nXB Configuration (Cumula 1400MHz)	ative aggre	egated BW	/channel	<=
1	n257, n258, n261	22.4	[8.2]	[5.0]	[9.2]- TT	43
1	n260	20.6	[8.2]	[5.0]	[7.4]- TT	43
2	n257, n258, n261	22.4	[9.3]	[5.0]	[8.1]- TT	43
2	n260	20.6	[9.3]	[5.0]	[6.3]- TT	43
3	n257, n258, n261	22.4	[8.0]	[5.0]	[9.4]- TT	43
3	n260	20.6	[8.0]	[5.0]	[7.6]- TT	43
4	n257, n258, n261	22.4	[9.2]	[5.0]	[8.2]- TT	43
4	n260	20.6	[9.2]	[5.0]	[6.4]- TT	43
5	n257, n258, n261	22.4	[11.2]	[7.0]	[4.2]- TT	43
5	n260	20.6	[11.2]	[7.0]	[2.4]- TT	43
Tes	t requirements for a CA_nXD, CA_ı	NXB Configuration (Cumulative ag	ggregated	BWchann	iel < 8001	MHz)
1	n257, n258, n261	22.4	7.7	[5.0]	[9.7]- TT	43
1	n260	20.6	7.7	[5.0]	[7.9]- TT	43
2	n257, n258, n261	22.4	7.5	[5.0]	[9.9]- TT	43
2	n260	20.6	7.5	[5.0]	[8.1]- TT	43
3	n257, n258, n261	22.4	8.7	[5.0]	[8.7]- TT	43
3	n260	20.6	8.7	[5.0]	[6.9]- TT	43
4	n257, n258, n261	22.4	10.7	[7.0]	[4.7]- TT	43
4	n260	20.6	10.7	[7.0]	[2.9]- TT	43
Test	t requirements for a CA_nXG, CA_r	nXO, CA_nXD Configuration (Cum 400MHz)	nulative ag	gregated	BWchan	nel <
1	n257, n258, n261	22.4	5	[4.0]	[13.4]- TT	43
1	n260	20.6	5	[4.0]	[11.6]- TT	43
2	n257, n258, n261	22.4	6.5	[5.0]	[10.9]- TT	43
2	n260	20.6	6.5	[5.0]	[9.1]- TT	43
3	n257, n258, n261	22.4	9	[5.0]	[8.4]- TT	43
3	n260	20.6	9	[5.0]	[6.6]- TT	43
O)	st requirements for a CA_nX(D-G) ) _UL_nXO, CA_nX(D-H)_UL_nXD, C X(D-Q)_UL_nXD, CA_nX(G-I)_UL_n	A_nX(D-P)_UL_nXD, CA_nX(E-O)	_UL_nXO,	ĊA_nX(D	-I)_UL_n	XD,
1	n257, n258, n261	22.4	[8.2]	[5.0]	[9.2]- TT	43
1	n260	20.6	[8.2]	[5.0]	[7.4]- TT	43
2	n257, n258, n261	22.4	[9.3]	[5.0]	[8.1]- TT	43
	n260	1	-		[6.3]-	

3         1237, 1238, 1261         22.4         [8.0]         [5.0]         [7.1]         43           3         n260         20.6         [8.0]         [5.0]         [7.6]-         43           4         n257, n258, n261         22.4         [9.2]         [5.0]         [7.1]-         43           5         n267, n258, n261         22.4         [9.2]         [5.0]         [7.4]-         43           5         n267, n258, n261         22.4         [11.2]         [7.0]         [4.2]-         43           5         n260         20.6         [11.2]         [7.0]         [7.4]-         43           7         n260         20.6         [11.2]         [7.0]         [7.4]-         43           7         n260         20.6         [11.2]         [7.0]         [7.4]-         43           1         n260, CA, nX(D-G), UL, nXD, CA, nX(D-C), UL, nXD, CA, nX(D-C), UL, nXD, CA, nX(D-C), UL, nXD, CA, nX(D-U), NC, CA, nX(D-U), UL, nXD, CA,	2	m0F7 m0F0 m0C1				[0,4]	
20.6         [6.0]         [5.0]         TT         4.3           4         n257, n258, n261         22.4         [9.2]         [5.0]         [8.2]         43           4         n260         20.6         [9.2]         [5.0]         [6.4]         T         43           5         n257, n258, n261         22.4         [11.2]         [7.0]         [4.2]         43           5         n260         20.6         [11.2]         [7.0]         [7.1]         43           7         Test requirements for a CA_nX(D-G)_UL_nXD, CA_nX(D-D)_UL_nXD, CA_nX(D-U)_UL_nXD, CA_nX(D-U)_T, T         43           1         n260         20.6         7.7         [5.0]         [9.7]         43           2         n257, n258, n261         22.4         7.5         [5.0]         [8.7]         43           3         n260         20.6         7.5         [5.0]         [8.7]         43           3         n267, n258, n261         22.4         8.7         [5.0]         [6.9]         7.7           4         n260 <td>3</td> <td>n257, n258, n261</td> <td>22.4</td> <td>[8.0]</td> <td>[5.0]</td> <td></td> <td>43</td>	3	n257, n258, n261	22.4	[8.0]	[5.0]		43
1         1	3	n260	20.6	[8.0]	[5.0]		43
20.0         [9.2]         [0.1]         TT         4.3           5         n257, n258, n261         22.4         [11.2]         [7.0]         [4.2]-         43           5         n260         20.6         [11.2]         [7.0]         [2.4]-         43           Test requirements for a CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_nX(O-G)_UL_nXG, CA_nX(D-J)_UL_NXG, CA_nX(O-J)_UL_NXG, CA_nX(O-J)_UL_NXG, CA_nX(O-J)_UL_NXD, CA_nX(O-J)_UL_NXD, CA_nX(O-J)_UL_NXD, CA_nX(CO-J)_UL_NXD, CA_nX(O-H)_UL_NXD, CA_nX(CO-J)_UL_NXD, CA_nX(O-H)_UL_NXD, CA_nX(O-H)_H         43           1         n260         20.6         7.7         [5.0]         [17.7]-         43           2         n267, n258, n261         22.4         7.5         [5.0]         [18.1]-         43           3         n260         20.6         7.5         [5.0]         [17.7]-         43           3         n260         20.6         8.7         [5.0]         [17.7]-         43           4         n260         20.6         8.7         [5.0]         [17.7]-         43           3         n260         20.6         8.7         [5.0]         [17.7]-	4	n257, n258, n261	22.4	[9.2]	[5.0]		43
1         22.4         [11.2]         [7.0] $^{+}{T^{+}}$ 43           5         n260         20.6         [11.2]         [7.0] $^{+}{T^{+}}$ 43           Test requirements for a CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D-G)_UL_nXD, CA_nX(D-F)_UL_nXD, CA_nX(O-F)_UL_nXD, CA_nX(D-F)_UL_nXD, CA_nX(O-F)_UL_nXD, CA_nF, F)         [9.7]         43           1         n260         20.6         7.7         [5.0]         [7]         43           2         n260         20.6         7.5         [5.0]         [8.7]         43           3         n267, n258, n261         22.4         8.7         [5.0]         [6]         1           4         n260         20.6         8.7         [5.0]         [7]         43           4         n260         20.6         10.7         [7.0]         [4]         1         43           4         n260         20.6         10.7         [7.0]	4	n260	20.6	[9.2]	[5.0]		43
20.6         [11.2]         [17.2] <td>5</td> <td>n257, n258, n261</td> <td>22.4</td> <td>[11.2]</td> <td>[7.0]</td> <td></td> <td>43</td>	5	n257, n258, n261	22.4	[11.2]	[7.0]		43
O UL_nXO, CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXO, CA_nX(D-I)_UL_nXO, CA_NX(II)_IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII	5	n260	20.6	[11.2]	[7.0]		43
1n26022.47.7[5.0] $\Gamma_{T}$ 432n257, n258, n26122.47.5[5.0] $[T,9]$ - T432n26020.67.5[5.0] $[T,T]$ 433n257, n258, n26122.48.7[5.0] $[T,T]$ 433n257, n258, n26122.48.7[5.0] $[T,T]$ 434n26020.68.7[5.0] $[T,T]$ 434n257, n258, n26122.410.7[7.0] $[T,T]$ 434n26020.610.7[7.0] $[T,T]$ 434n26020.610.7[7.0] $[T,T]$ 434n26020.610.7[7.0] $[T,T]$ 431n26020.610.7[7.0] $[T,T]$ 431n26020.65[4.0] $[T,1]$ 432n257, n258, n26122.45[4.0] $[T,1]$ 432n257, n258, n26122.46.5[5.0] $[T,1]$ 432n26020.66.5[5.0] $[T,1]$ 433n257, n258, n26122.49[5.0] $[10.9]$ 432n26020.66.5[5.0] $[10.9]$ 433n257, n258, n26122.49[5.0] $[10.9]$ 433n257, n258, n26122.49[5.0] $[10.9]$ 43	0	)_UL_nXO, CA_nX(D-H)_UL_nXD, CA	_nX(D-P)_UL_nXD, CA_nX(O-E)_l	JL_nXO,	CA_nX(D	-I)_UL_n	хD,
20.67.7[5.0] $^{7}$ T <sup>2</sup> 432n257, n258, n26122.47.5[5.0] $^{17}$ T432n26020.67.5[5.0] $^{18}$ T433n257, n258, n26122.48.7[5.0] $^{18}$ T433n26020.68.7[5.0] $^{18}$ T434n26020.68.7[5.0] $^{16}$ .9]434n26020.610.7[7.0] $^{14}$ T434n26020.610.7[7.0] $^{12}$ .9]434n26020.610.7[7.0] $^{12}$ .9]43Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative aggregated BWchannel < 400MHz)	1	n257, n258, n261	22.4	7.7	[5.0]		43
2         n260         22.4         7.5         [5.0] $T_{TT}$ 43           3         n257, n258, n261         20.6         7.5         [5.0] $T_{TT}$ 43           3         n260         20.6         8.7         [5.0] $T_{TT}$ 43           3         n260         20.6         8.7         [5.0] $T_{TT}$ 43           4         n257, n258, n261         22.4         10.7         [7.0] $T_{TT}$ 43           4         n260         20.6         10.7         [7.0] $T_{TT}$ 43           4         n260         20.6         10.7         [7.0] $T_{TT}$ 43           4         n260         20.6         10.7         [7.0] $T_{TT}$ 43           Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative equative equativ	1	n260	20.6	7.7	[5.0]		43
3       n257, n258, n261       22.4       8.7       [5.0]       ITT       43         3       n260       20.6       8.7       [5.0]       ITT       43         4       n257, n258, n261       20.6       8.7       [5.0]       ITT       43         4       n257, n258, n261       22.4       10.7       [7.0]       ITT       43         4       n260       20.6       10.7       [7.0]       ITT       43         Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative aggregated BWchannel < 400MHz)	2	n257, n258, n261	22.4	7.5	[5.0]		43
$22.4$ $8.7$ $[5.0]$ $T_{T}$ $43$ $3$ $n260$ $20.6$ $8.7$ $[5.0]$ $T_{T}$ $43$ $4$ $n257, n258, n261$ $22.4$ $10.7$ $[7.0]$ $T_{T}$ $43$ $4$ $n260$ $20.6$ $10.7$ $[7.0]$ $T_{T}$ $43$ $4$ $n260$ $20.6$ $10.7$ $[7.0]$ $T_{T}$ $43$ $Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration(Cumulative aggregated BWchannel < 400MHz)1n257, n258, n26122.45[4.0][13.4]^-TT431n26020.65[4.0][11.6]^-TT432n257, n258, n26122.46.5[5.0][10.9]^-TT432n26020.66.5[5.0][9.1]^-T433n257, n258, n26122.49[5.0][8.4]^ 43$	2	n260	20.6	7.5	[5.0]		43
$20.6$ $8.7$ $[5.0]$ $^{1}$ TT $4.3$ 4 $n257, n258, n261$ $22.4$ $10.7$ $[7.0]$ $[4.7]$ - TT $43$ 4 $n260$ $20.6$ $10.7$ $[7.0]$ $[2.9]$ - TT $43$ Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative aggregated BWchannel < $400MHz$ )1 $n257, n258, n261$ $22.4$ $5$ $[4.0]$ $[13.4]$ - TT $43$ 1 $n260$ $20.6$ $5$ $[4.0]$ $[11.6]$ - TT $43$ 2 $n257, n258, n261$ $22.4$ $6.5$ $[5.0]$ $[10.9]$ - TT $43$ 2 $n260$ $20.6$ $6.5$ $[5.0]$ $[10.9]$ - TT $43$ 3 $n257, n258, n261$ $22.4$ $9$ $[5.0]$ $[9.1]$ - TT $43$	3	n257, n258, n261	22.4	8.7	[5.0]		43
4       n260       20.6       10.7       [7.0]       TT*       43         4       n260       20.6       10.7       [7.0]       TT*       43         Test requirements for a CA_nX(D-O)_UL_nXD, CA_nX(D-O)_UL_nXO Configuration (Cumulative aggregated BWchannel < 400MHz)       5       [4.0]       [13.4]-TT       43         1       n257, n258, n261       22.4       5       [4.0]       [11.6]-TT       43         2       n257, n258, n261       20.6       5       [4.0]       [11.6]-TT       43         2       n257, n258, n261       20.6       5       [5.0]       [10.9]-TT       43         2       n257, n258, n261       22.4       6.5       [5.0]       [10.9]-TT       43         3       n257, n258, n261       22.4       9       [5.0]       [8.4]-       43	3	n260	20.6	8.7	[5.0]		43
Image: Constraint of the constrated of the constraint of the constraint of the constraint of the	4	n257, n258, n261	22.4	10.7	[7.0]		43
BWchannel < 400MHz)           1         n257, n258, n261         22.4         5         [4.0]         [13.4]- TT         43           1         n260         20.6         5         [4.0]         [11.6]- TT         43           2         n257, n258, n261         22.4         6.5         [5.0]         [10.9]- TT         43           2         n260         20.6         6.5         [5.0]         [11.4]- TT         43           3         n257, n258, n261         22.4         9         [5.0]         [8.4]- TT         43				-		TT	-
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Test	requirements for a CA_nX(D-O)_UL_		guration	(Cumulat	ive aggre	gated
2     n257, n258, n261     22.4     6.5     [4.0]     TT <sup>-</sup> 43       2     n260     20.6     6.5     [5.0]     TT     43       3     n257, n258, n261     22.4     9     [5.0]     [10.9]- TT     43	1	n257, n258, n261		5	[4.0]		43
2     n260     20.6     6.5     [5.0]     TT     43       3     n257, n258, n261     22.4     9     [5.0]     [9.1]- TT     43	1	n260	20.6	5	[4.0]		43
20.6     6.5     [5.0]     TT     43       3     n257, n258, n261     22.4     9     [5.0]     [8.4]-     43	2	n257, n258, n261	22.4	6.5	[5.0]		43
	2	n260	20.6	6.5	[5.0]	[9.1]-	43
	3	n257, n258, n261	22.4	9	[5.0]		43
3 n260 20.6 9 [5.0] [6.6]- TT 43	3	n260	20.6	9	[5.0]		43
NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-13.	NOTE	1: TT for each band and accumulative	e aggregated bandwidth is specified	in Table	6.2A.2.1.5	-13.	

### Table 6.2A.2.1.5-12: MPR requirements for Intra-band Contiguous UL CA (Power Class 3, Noncontiguous allocation)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
	Test require	ements for a CA_nX	B, CA_nXD,	, CA_XG, CA_ı	nXO Configuration	
1	n257, n258, n261	22.4	7	[5.0]	[10.4]-TT	43
1	n260	20.6	7	[5.0]	[8.6]-TT	43
2	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
2	n260	FFS	FFS	FFS	FFS	FFS
3	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
3	n260	FFS	FFS	FFS	FFS	FFS
NOTE 1	TT for each band and	d accumulative agore	aated band	width is specifie	d in Table 6.2A.2.1.	5-13.

### Table 6.2A.2.1.5-13: Test Tolerance (MPR for CA for Power class 3) (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	3.11 dB	3.11 dB

# Table 6.2A.2.1.5-14: MPR requirements for Intra-band Contiguous UL CA (Power Class 4, single CC MPR requirement)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
Test	requirements for a C	A_nXG, CA_nXO Cor	figuration (	Cumulative ag	gregated BWchan	nel <= 200MHz)
1	n257, n258, n261	34	0	0	34.0-TT	43
1	n260	31	0	0	31.0-TT	43
2	n257, n258, n261	34	2	[1.5]	[30.5]-TT	43
2	n260	31	2	[1.5]	[27.5]-TT	43
•	Test requirements fo	or a CA_nXD Configur	ation (Cum	ulative aggreg	ated BWchannel <	= 400MHz)
1	n257, n258, n261	34	0	0	34.0-TT	43
1	n260	31	0	0	31.0-TT	43
2	n257, n258, n261	34	3	[2.0]	[29.0]-TT	43
2	n260	31	3	[2.0]	[26.0]-TT	43
NOTE 1	: TT for each band a	nd accumulative aggre	gated band	vidth is specifie	d in Table 6.2A.2.1.	5-17.

Table 6.2A.2.1.5-15: MPR requirements for Intra-band Contiguous UL CA (Power Class 4, MPRc\_CA)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
Tes	t requirements for a CA_nXB, nX0	C_UL_nXB Configuration (Cumul 1400MHz)	ative aggre	egated BV	Vchannel	<=
1	n257, n258, n261	34	[8.2]	[5.0]	[20.8]- TT	43
1	n260	31	[8.2]	[5.0]	[17.8]- TT	43
2	n257, n258, n261	34	[9.3]	[5.0]	[19.7]- TT	43
2	n260	31	[9.3]	[5.0]	[16.7]- TT	43
3	n257, n258, n261	34	[8.0]	[5.0]	[21.0]- TT	43
3	n260	31	[8.0]	[5.0]	[18.0]- TT	43
4	n257, n258, n261	34	[9.2]	[5.0]	[19.8]- TT	43
4	n260	31	[9.2]	[5.0]	[16.8]- TT	43
5	n257, n258, n261	34	[11.2]	[7.0]	[15.8]- TT	43
5	n260	31	[11.2]	[7.0]	[12.8]- TT	43
Test	requirements for a CA_nXD, CA_r	XB Configuration (Cumulative a	ggregated	BWchann		MHz)
1	n257, n258, n261	34	7.7	[5.0]	[21.3]- TT	43
1	n260	31	7.7	[5.0]	[18.3]- TT	43
2	n257, n258, n261	34	7.5	[5.0]	[21.5]- TT	43
2	n260	31	7.5	[5.0]	[18.5]- TT	43
3	n257, n258, n261	34	8.7	[5.0]	[20.3]- TT	43
3	n260	31	8.7	[5.0]	[17.3]- TT	43
4	n257, n258, n261	34	10.7	[7.0]	[16.3]- TT	43
4	n260	31	10.7	[7.0]	[13.3]- TT	43
Test	requirements for a CA_nXG, CA_n	XO, CA_nXD Configuration (Cun 400MHz)	nulative ag	gregated	BWchan	nel <
1	n257, n258, n261	34	5	[4.0]	[25.0]- TT	43
1	n260	31	5	[4.0]	[22.0]- TT	43
2	n257, n258, n261	34	6.5	[5.0]	[22.5]- TT	43
2	n260	31	6.5	[5.0]	[19.5]- TT	43
3	n257, n258, n261	34	9	[5.0]	[20.0]- TT	43
3	n260	31	9	[5.0]	[17.0]- TT	43
O)_	requirements for a CA_nX(D-G) )_ UL_nXO, CA_nX(D-H)_UL_nXD, C. (D-Q)_UL_nXD, CA_nX(G-I)_UL_n	A_nX(D-P)_UL_nXD,	_UL_nXO,	CA_nX(D	-I)_UL_n	XD,
1	n257, n258, n261	34	[8.2]	[5.0]	[20.8]- TT	43
1	n260	31	[8.2]	[5.0]	[17.8]- TT	43
2	n257, n258, n261	34	[9.3]	[5.0]	[19.7]- TT	43
2	n260	31	[9.3]	[5.0]	[16.7]-	43

3	n257, n258, n261	34	[8.0]	[5.0]	[21.0]- TT	43	
3	n260	31	[8.0]	[5.0]	[18.0]- TT	43	
4	n257, n258, n261	34	[9.2]	[5.0]	[19.8]- TT	43	
4	n260	31	[9.2]	[5.0]	[16.8]- TT	43	
5	n257, n258, n261	34	[11.2]	[7.0]	[15.8]- TT	43	
5	n260	31	[11.2]	[7.0]	[12.8]- TT	43	
0	Test requirements for a CA_nX(D-G)_UL_nXD, CA_nX(D-O)_UL_nXD, CA_nX(D-G)_UL_nXG, CA_nX(D- O)_UL_nXO, CA_nX(D-H)_UL_nXD, CA_nX(D-P)_UL_nXD, CA_nX(O-E)_UL_nXO, CA_nX(D-I)_UL_nXD, CA_nX(D-Q)_UL_nXD, CA_nX(G-I)_UL_nXG Configuration (Cumulative aggregated BWchannel < 800MHz)						
1	n257, n258, n261	34	7.7	[5.0]	[21.3]- TT	43	
1	n260	31	7.7	[5.0]	[18.3]- TT	43	
2	n257, n258, n261	34	7.5	[5.0]	[21.5]- TT	43	
2	n260	31	7.5	[5.0]	[18.5]- TT	43	
3	n257, n258, n261	34	8.7	[5.0]	[20.3]- TT	43	
3	n260	31	8.7	[5.0]	[17.3]- TT	43	
4	n257, n258, n261	34	10.7	[7.0]	[16.3]- TT	43	
4	n260	31	10.7	[7.0]	[13.3]- TT	43	
Test	t requirements for a CA_nX(D-O)_UL_	_nXD, CA_nX(D-O)_UL_nXO Config BWchannel < 400MHz)	guration	(Cumulat	ive aggre	gated	
1	n257, n258, n261	34	5	[4.0]	[25.0]- TT	43	
1	n260	31	5	[4.0]	[22.0]- TT	43	
2	n257, n258, n261	34	6.5	[5.0]	[22.5]- TT	43	
2	n260	31	6.5	[5.0]	[19.5]- TT	43	
3	n257, n258, n261	34	9	[5.0]	[20.0]- TT	43	
3	n260	31	9	[5.0]	[17.0]- TT	43	
NOTE	1: TT for each band and accumulative	e aggregated bandwidth is specified	in Table	6.2A.2.1.5	-17.		

Table 6.2A.2.1.5-16: MPR requirements for Intra-band Contiguous UL CA (Power Class 4, Non-
contiguous allocation)

Test ID	Band	Min peak EIRP (dBm)	MPR (dB)	T(MPR) (dB)	Lower limit (dBm)	Upper limit (dBm)
	Test requirements for a CA_nXB, CA_nXD, CA_XG, CA_nXO Configuration					
1	n257, n258, n261	34	7	[5.0]	[22.0]-TT	43
1	n260	31	7	[5.0]	[19.0]-TT	43
2	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
2	n260	FFS	FFS	FFS	FFS	FFS
3	n257, n258, n261	FFS	FFS	FFS	FFS	FFS
3	n260	FFS	FFS	FFS	FFS	FFS
NOTE 1	NOTE 1: TT for each band and accumulative aggregated bandwidth is specified in Table 6.2A.2.1.5-17.					

Table 6.2A.2.1.5-17: Test Tolerance (MPR for CA for Power class 4)

# 6.2A.3 UE maximum output power with additional requirements for CA

FFS

# 6.2A.4 Configured transmitted power for CA

# 6.2A.4.0 Minimum conformance requirements

A UE configured with carrier aggregation can configure its maximum output power for each uplink carrier f of activated serving cell c and its total configured output power  $P_{CMAX}$ . The definition of the configured UE maximum output power  $P_{CMAX,f,c}$  for each carrier f of a serving cell c is used for power headroom reporting for carrier f of serving cell c only and is in accordance with that specified in clause 6.2.4 with parameters MPR, A-MPR and P-MPR replaced with those specified below. The total configured power  $P_{CMAX}$  in a transmission occasion is the sum of the configured power for carrier f of serving cell c with non-zero granted transmission power in the respective reference point.

For uplink intra-band contiguous carrier aggregation, MPR is specified in subclause 6.2A.2.  $P_{CMAX}$  is calculated under the assumption that power spectral density for each RB in each component carrier is same.

The total configured UE maximum output power  $P_{CMAX}$  shall be set such that the corresponding measured total peak EIRP  $P_{UMAX}$  is within the following bounds

 $P_{Powerclass} - MAX(MAX(MPR, A\_MPR), P-MPR) - MAX\{T(MAX(MPR, A\_MPR)), T(P-MPR)\} \leq P_{UMAX} \leq EIRP_{max} = P_{MAX} + P_{MAX}$ 

with  $P_{Powerclass}$  the UE power class as specified in sub-clause 6.2A.1, EIRP<sub>max</sub> the applicable maximum EIRP as specified in sub-clause 6.2A.1, MPR as specified in sub-clause 6.2A.2, A-MPR as specified in sub-clause 6.2A.3, P-MPR the power management term for the UE as described in 6.2.4 and TRP<sub>max</sub> the maximum TRP for the UE power class as specified in sub-clause 6.2A.1.

 $P_{UMAX}$  is defined as  $10*log10(\sum p_{UMAX,fli),c(j)})$  for each carrier f (i=1...n) and serving cell c (j=1...m) where  $p_{UMAX,fli),c(j)}$  is linear value of  $P_{UMAX,fli),c(j)}$ 

The tolerance  $T(\Delta P)$  for applicable values of  $\Delta P$  (values in dB) is specified in Table 6.2A.4-1.

Operating Band	∆ <b>P (dB)</b>	Tolerance T(∆P) (dB)			
	$\Delta P = 0$	0			
	0 < ∆P ≤ 2	[1.5]			
	2 < ∆P ≤ 3	[2.0]			
n257, n258, n260,	3 < ∆P ≤ 4	[3.0]			
n261	4 < ∆P ≤ 5	[4.0]			
	5 < ∆P ≤ 10	[5.0]			
	10 < ∆P ≤ 15	[7.0]			
	15 < ∆P ≤ X	[8.0]			
NOTE: X is the value such that $P_{umax}$ lower bound, $P_{Powerclass} - \Delta P$					
$- T(\Delta P) = minimum output power specified in subclause$					
6.3A.1					

# Table 6.2A.4-1: PUMAX tolerance

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2A.4.

# 6.2A.4.1 Configured transmitted power for CA (2UL CA)

# 6.2A.4.1.1 Test purpose

To verify the UE transmitted power  $P_{\text{UMAX}}$  is within the range defined prescribed by the specified nominal maximum output power and tolerance.

# 6.2A.4.1.2 Test applicability

The requirements of this test are covered in test cases 6.2A.1.1.1 UE maximum output power - EIRP and TRP for CA (2UL CA), 6.2A.2.1 Maximum output power reduction for CA (2UL CA) and 6.2A.3.1 UE maximum output power with additional requirements for CA (2UL CA) to all types of NR UE release 15 and forward supporting 2UL CA.

### 6.2A.4.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.2A.4.0.

## 6.2A.4.1.4 Test description

This test is covered by clause 6.2A.1.1.1 UE maximum output power - EIRP and TRP for CA (2UL CA), 6.2A.2.1 Maximum output power reduction for CA (2UL CA) and 6.2A.3.1 UE maximum output power with additional requirements for CA (2UL CA).

## 6.2A.4.1.5 Test requirements

This test is covered by clause 6.2A.1.1.1 UE maximum output power - EIRP and TRP for CA (2UL CA), 6.2A.2.1 Maximum output power reduction for CA (2UL CA) and 6.2A.3.1 UE maximum output power with additional requirements for CA (2UL CA).

# 6.2D Transmit power for UL MIMO

# 6.2D.1 UE maximum output power for UL MIMO

FFS

# 6.2D.2 UE maximum output power reduction for UL MIMO

FFS

6.2D.3 UE maximum output power with additional requirements for UL MIMO

FFS

# 6.2D.4 Configured transmitted power for UL MIMO

# 6.2D.4.1 Test purpose

To verify the UE transmitted power  $P_{UMAX,f,c}$  is within the range defined prescribed by the specified nominal maximum output power and tolerance.

#### 6.2D.4.2 Test applicability

The requirements of this test are covered in test cases 6.2D.1 UE Maximum output power for UL MIMO, 6.2D.2 UE maximum output power reduction forUL MIMO and 6.2D.3 UE Maximum output power with additional requirements for UL MIMO to all types of NR UE release 15 and forward that supports UL MIMO.

#### 6.2D.4.3 Minimum conformance requirements

For UE configured with ULMIMO, the configured maximum output power  $P_{CMAX,c}$  for serving cell c is defined as sum of all streams and is bound by limits set in section 6.2.4.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.2D.4.

#### 6.2D.4.4 Test description

This test is covered by clause 6.2D.1 UE Maximum output power for UL MIMO, 6.2D.2 UE maximum output power reduction forUL MIMO and 6.2D.3 UE Maximum output power with additional requirements for UL MIMO.

### 6.2D.4.5 Test requirements

This test is covered by clause 6.2D.1 UE Maximum output power for UL MIMO, 6.2D.2 UE maximum output power reduction forUL MIMO and 6.2D.3 UE Maximum output power with additional requirements for UL MIMO.

# 6.3 Output power dynamics

# 6.3.1 Minimum output power

Editor's Note: The following aspects of the clause are for future consideration:- Testing of extreme conditions for FR2 is FFS.

### 6.3.1.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

#### 6.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.3.1.3 Minimum conformance requirements

The minimum controlled output power of the UE is defined as the EIRP in the channel bandwidth for all transmit bandwidth configurations (resource blocks) when the power is set to a minimum value.

The minimum output power is defined as the mean power in at least one subframe (1ms).

#### 6.3.1.3.1 Minimum output power for power class 1

For power class 1 UE, the minimum output power shall not exceed the values specified in Table 6.3.1.3.1-1 for each operating band supported. The minimum power is verified in beam locked mode with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4	47.58
	100	4	95.16
	200	4	190.20
	400	4	380.28

 Table 6.3.1.3.1-1: Minimum output power for power class 1

## 6.3.1.3.2 Minimum output power for power class 2, 3, and 4

The minimum output power shall not exceed the values specified in Table 6.3.1.3.2-1 for each operating band supported. The minimum power is verified in beam locked mode with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13	47.58
[	100	-13	95.16
Ī	200	-13	190.20
Ī	400	-13	380.28
NOTE 1: n260 is not appl	ied for power class 2.	-	

Table 6.3.1.3.2-1: Minimum output power for power class 2, 3, and 4

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.1.

### 6.3.1.4 Test description

#### 6.3.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in Table 6.3.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

## Table 6.3.1.4.1-1: Test Configuration Table

	Initia	I Conditions		
Test Environment as specified in TS 38.508-1 [10] subclause 4.1		Normal		
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1		Low range, Mid range, High range		
Test Channel Bandwidths as specified in TS 38.508-		Lowest, Mid, Highest		
1 [10] subclause 4.3.1				
Test SCS	as specified in Table 5.3.5-1.	Highest		
	Test	Parameters		
	Downlink Configuration	Uplink Configuration		
Test ID	N/A for minimum output power test case	Modulation	RB allocation (NOTE 1)	
1		DFT-s-OFDM QPSK Outer_Full		
	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.			

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.1.4.3.

#### 6.3.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.1.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "down" commands in every uplink scheduling information to the UE; allow at least 200ms starting from the first TPC command in this step to ensure that the UE transmits at its minimum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP in the Tx beam peak direction in the measurement bandwidth specified in Table 6.3.1.5-1 and Table 6.3.1.5-2 for the specific channel bandwidth under test. EIRP test procedure is defined in Annex K.1.3. The measuring duration is at least one active subrame (1ms). EIRP is calculated considering both polarizations, theta and phi. For TDD, only slots consisting of only UL symbols are under test.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.3.1.5 Test requirement

The maximum EIRP, derived in step 5 shall not exceed the values specified in Table 6.3.1.5-1 and Table 6.3.1.5-2.

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

## Table 6.3.1.5-1: Minimum output power for power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n261	50	-13+TT	47.58
	100	-13+2.4+TT	95.16
	200	-13+5.4+TT	190.20
	400	-13+8.4+TT	380.28
n260	50	-13+4.5+TT	47.58
	100	-13+7.5+TT	95.16
	200	-13+10.5+TT	190.20
	400	-13+13.5+TT	380.28
		stability issue and test requirem asurement result = 1.0 dB (Mini	

#### Table 6.3.1.5-3: Minimum output power Test tolerance for power class 1

# FFS

#### Table 6.3.1.5-4: Minimum output power Test tolerance for power class 2, 3, 4

Test Metric	23.45GHz ≤ f ≤ 32.125GHz	32.125GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)	3.35 dB	3.35 dB

# 6.3.2 Transmit OFF power

Editor's note: Following aspects are either missing or not yet determined otherwise:

- Measurement grid for PC2/4 in Annex M.4 is TBD.
- The testability of this test case is pending further analysis on relaxation of the requirement for other than Band n257.

### 6.3.2.1 Test purpose

To verify that the UE transmit OFF power is lower than the value specified in the test requirement.

#### 6.3.2.2 Test applicability

This test applies to all types of NR UE release 15 and forward.

NOTE: Currently, this test case can only support Band n257 and PC3.

#### 6.3.2.3 Minimum conformance requirements

The transmit OFF power is defined as the TRP in the channel bandwidth when the transmitter is OFF. The transmitter is considered OFF when the UE is not allowed to transmit on any of its ports.

The transmit OFF power shall not exceed the values specified in Table 6.3.2.3-1 for each operating band supported. The requirement is verified with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

#### Table 6.3.2.3-1: Transmit OFF power

Operating band	Channel bandwidth / Transmit OFF power (dBm) / measurement bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n259,n261	-35	-35	-35	-35
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.2.

An excess transmit OFF power potentially increases the Rise Over Thermal (RoT) and therefore reduces the cell coverage area for other UEs.

### 6.3.2.4 Test description

#### 6.3.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initial Conditions						
Test Enviro subclause	onment as specified in 4.1	TS 38.508-1 [10]	Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			[10] Low range, Mid range, High range				
Test Channel Bandwidths as specified in TS 38.508- 1 [10] subclause 4.3.1		Lowest					
Test SCS as specified in Table 5.3.5-1.			Highest				
Test			Parameters				
	Downlink C	onfiguration	Up	link Configuration			
Test ID	Modulation	RB allocation	Modulation RB allocation				
1	N/A	0	N/A 0				

## Table 6.3.2.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channels are set according to Table 6.3.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity NR, Connected without release On, Test Mode On and Test Loop Function On according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.2.4.3.

#### 6.3.2.4.2 Test procedure

- 1. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE) for the UE Tx beam selection to complete.
- 2. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 3. Measure UE TRP for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.3.2.5-1. Total radiated power is measured according to TRP measurement procedure defined in Annex K. TRP is calculated considering both polarizations, theta and phi.

NOTE : The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.3.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.3.2.5 Test requirement

The requirement for the transmit OFF power shall not exceed the values specified in Table 6.3.2.5-1.

Operating band	Channel bandwidth / Transmit OFF power (dBm) / measurement bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
n257 <sup>2</sup>	-35+21.4	-35+24.4	-35+27.4	-35+30.4		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
n258, n261	-35+[21.4]	-35+[24.4]	-35+[27.4]	-35+[30.4]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
n260	-35+[24.1]	-35+[27.1]	-35+[30.1]	-35+[33.1]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
NOTE 1: Core requirement cannot be tested due to testability issue and test requirement includes relaxation to achieve impact from test system noise to measurement result = 1.0 dB (Minimum requirement + relaxation).						
NOTE 2: Relaxed n257 test requirement is testable for PC3.						

Table 6.3.2.5-1: Transmit OFF power

# 6.3.3 Transmit ON/OFF time mask

# 6.3.3.1 General

The transmit ON/OFF time mask defines the transient period(s) allowed

- between transmit OFF power and transmit ON power symbols (transmit ON/OFF)
- between continuous ON-power transmissions when power change or RB hopping is applied.

In case of RB hopping, transition period is shared symmetrically.

Unless otherwise stated the minimum requirements in clause 6.5 apply also in transient periods.

The transmit ON/OFF time mask is defined as a directional requirement. The requirement is verified in beam locked mode at beam peak direction. The maximum allowed EIRP OFF power level is -30dBm at beam peak direction. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

In the following sub-clauses, following definitions apply:

- A slot transmission is a Type A transmission.
- A long subslot transmission is a Type B transmission with more than 2 symbols.
- A short subslot transmission is a Type B transmission with 1 or 2 symbols.

# 6.3.3.2 General ON/OFF time mask

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.

#### 6.3.3.2.1 Test purpose

To verify that the general ON/OFF time mask meets the requirements given in 6.3.3.2.5.

The transmit ON/OFF time mask defines the transient period(s) allowed

- between transmit OFF power and transmit ON power symbols (transmit ON/OFF)

Unless otherwise stated the minimum requirements in clause 6.5 apply also in transient periods.

Transmission of the wrong power increases interference to other channels, or increases transmission errors in the uplink channel.

# 6.3.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

## 6.3.3.2.3 Minimum conformance requirements

The transmit ON/OFF time mask is defined as a directional requirement. The requirement is verified in beam locked mode at beam peak direction. The maximum allowed EIRP OFF power level is -30dBm at beam peak direction. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle)

The general ON/OFF time mask defines the observation period allowed between transmit OFF and ON power. ON/OFF scenarios include: contiguous, and non-contiguous transmission, etc.

The OFF power measurement period is defined in a duration of at least one slot excluding any transient periods. The ON power is defined as the mean power over one slot excluding any transient period.





The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.3.2.

6.3.3.2.4 Test description

# 6.3.3.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3.3.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initia	I Conditions			
Test Environment as specified in TS 38.508-1 [10]		Normal			
subclause	4.1				
Test Freque	uencies as specified in TS 38.508-1 [10] 4.3.1	Low range, Mid range, High range			
Test Channel Bandwidths as specified in TS 38.508- 1 [10] subclause 4.3.1		Lowest, Mid, Highest			
Test SCS	as specified in Table 5.3.5-1.	Highest			
	Test	Parameters			
	Downlink Configuration	Uplin	k Configuration		
Test ID	N/A for maximum output power test case	Modulation RB allocation (NOTE 1)			
1	1 DFT-s-OFDM QPSK Outer_Full				
	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.				

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channels are set according to Table 6.3.3.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.3.2.4.3.

#### 6.3.3.2.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 with TPC command 0dB for C\_RNTI to schedule the UL RMC according to Table 6.3.3.2.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 4) for the UE Tx beam selection to complete.
- 3. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 4. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the slot prior to the PUSCH transmission, excluding a transient period of 5 µs in the end of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 5. For UE transmission ON power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-2. EIRP test procedure is defined in Annex K. The period of the measurement shall be one slot with PUSCH transmission. EIRP is calculated considering both polarizations, theta and phi. For TDD, only slots consisting of only UL symbols are under test.
- 6. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-1. EIRP test procedure is defined in Annex K.1.3 The period of the measurement shall be the slot following the PUSCH transmission, excluding a transient period of 5 μs at the beginning of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 7. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

#### 6.3.3.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions.

Information Element	Value/remark	Comment	Condition
PUSCH-ConfigCommon ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0- PUSCH-AlphaSets)) OF SEQUENCE {	1 entry		
p0-NominalWithGrant	-102		50MHz
	-106		100MHz
	-108		200MHz
	-112		400MHz
alpha	alpha1		
}			
}			

# Table 6.3.3.2.4.3-1: PUSCH-ConfigCommon

# Table 6.3.3.2.4.3-2: ServingCellConfigCommon

Derivation Path: 38.508-1[5], Table 4.6.3-168			
Information Element	Value/remark	Comment	Condition
ServingCellConfigCommon ::= SEQUENCE {			
ss-PBCH-BlockPower	1		SCS_60kHz
	4		SCS_120kH
			Z
}			

Condition	Explanation
SCS_60kHz	SCS=60kHz for SS/PBCH block
SCS_120kHz	SCS=120kHz for SS/PBCH block

# 6.3.3.2.5 Test requirement

The requirement for the EIRP measured in steps 4, 5 and 6 of the test procedure shall not exceed the values specified in Table 6.3.3.2.5-1 and 6.3.3.2.5-2.

# Table 6.3.3.2.5-1: Test requirement of OFF power of General ON/OFF time mask

	Channel bandwidth / minimum output power / measurement bandwidth					
	50 MHz	50 MHz 100 MHz 200 MHz 400				
Transmit OFF power		≤ -30+TT+R dBm				
Transmission OFF Measurement bandwidth	47.58 MHz	95.16 MHz 190.20 MHz 380.28 M				
NOTE 1: Core requirement cannot be tested due to testability issue and test requirement includes relaxation to achieve impact from test system noise to measurement result = 1.0 dB (Minimum requirement + relaxation R).         NOTE 2: Relaxation R is specified in Table 6.3.3.2.5-5.						

	SCS	Channel bandwidth / measurement bandwidth			ement
	[kHz]	50 MHz	100 MHz	200 MHz	400 MHz
Expected Transmission ON	60	22.1	21.1	22.1	N/A
power for DFT-s- OFDM	120	22.1	21.1	22.1	21.1
Power toleran	ce	± (14+TT)dB			
Note 1: The lowe	er power limit shall not exceed the minimum output power				utput power
requirements defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2.1.3.					

# Table 6.3.3.2.5-2: Test requirement of ON power of General ON/OFF time mask

## Table 6.3.3.2.5-3: Test Tolerance for OFF power

#### FFS

## Table 6.3.3.2.5-4: Test Tolerance for ON power

FFS

Operating band	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n261	19.4 dB	22.4 dB	25.4 dB	28.4 dB
n260	21.5 dB	24.5 dB	27.5 dB	30.5 dB

# 6.3.3.3 Transmit power time mask for slot and short or long subslot boundaries

No test case details are specified. Current test procedures for time masks are based on power measurement in relatively long period compared with transient period. For time masks between 2 active time slots with different power level, the test procedure can't provide enough resolution to identify non-conformant UEs. Therefore the minimum requirement is not testable.

# 6.3.3.4 PRACH time mask

Editor's Notes: This clause is incomplete. The following aspects are either missing or not yet determined:

- Message contents are not complete
- Measurement uncertainty and Test tolerance are not complete
- Test requirements are not complete
- PRACH configuration index is not complete
- The further investigation is essential that how does beamforming affect the initial access procedure

#### 6.3.3.4.1 Test purpose

To verify that the PRACH time mask meets the requirements given in 6.3.3.4.5.

The time mask for PRACH time mask defines the transient period(s) allowed between transmit OFF power and transmit ON power when transmitting the PRACH.

Transmission of the wrong power increases interference to other channels, or increases transmission errors in the uplink channel.

#### 6.3.3.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

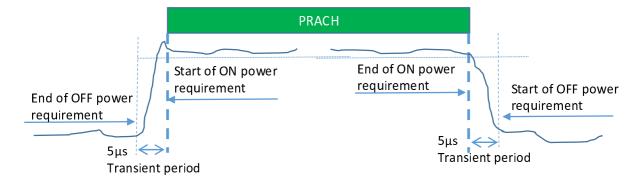
#### 6.3.3.4.3 Minimum conformance requirements

The transmit ON/OFF time mask is defined as a directional requirement. The requirement is verified in beam locked mode at beam peak direction. The maximum allowed EIRP OFF power level is -30dBm at beam peak direction. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

The PRACH ON power is specified as the mean power over the PRACH measurement period excluding any transient periods as shown in Figure 6.3.3.4.3-1. The measurement period for different PRACH preamble format is specified in Table 6.3.3.4.3-1.

Format	SCS	Measurement period	
A1	60 kHz	0.035677 ms	
71	120 kHz	0.017839 ms	
٥	60 kHz	0.071354 ms	
A <sub>2</sub>	120 kHz	0.035677 ms	
A <sub>3</sub>	60 kHz	0.107031 ms	
A3	120 kHz	0.053516 ms	
B1	60 kHz	0.035091 ms	
D1	120 kHz	0.0175455 ms	
B4	60 kHz	0.207617 ms	
D4	120 kHz	0.103809 ms	
	60 kHz	0.035677 ms for front X1 occasion	
		0.035091 ms for last occasion	
A1/B1		X1 = [2,5]	
Al/D	120 kHz	0.017839 ms for front X1occasion	
		0.017546 ms for last occasion	
		X1 = [2,5]	
	60 kHz	0.071354 ms for front X2 occasion	
		0.069596 ms for last occasion	
A <sub>2</sub> /B <sub>2</sub>		X2 = [1,2]	
1 12/ 02	120 kHz	0.035677 ms for front X2 occasion	
		0.034798 ms for last occasion	
		X2 = [1,2]	
	60 kHz	0.107031 ms for first occasion	
A <sub>3</sub> /B <sub>3</sub>		0.104101 ms for second occasion	
10 - 0	120 kHz	0.053515 ms for first occasion	
		0.052050 ms for second occasion	
Co	60 kHz	0.026758 ms	
•••	120 kHz	0.013379 ms	
C <sub>2</sub>	60 kHz	0.083333 ms	
120 kHz 0.0416667 ms			
		ACH occasion start from begin of 0ms or 0.5ms	
b	oundary, the m	neasurement period will plus 0.032552µs	

Table 6.3.3.4.3-1: PRACH ON power measurement period





The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.3.4.

# 6.3.3.4.4 Test description

# 6.3.3.4.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3.3.4.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.3.3.4.4.1-1: Test Configuration Table

Initial Conditions				
Test Environment as specified in TS 38.508-1 [10] subclause 4.1	TBD			
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1	Mid range			
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1	Lowest, Mid, Highest			
Test SCS as specified in Table 5.3.5-1	SCS defined in TS 38.211 [8] subclause 6.3.3.2			
PRACH preamble format				
PRACH Configuration Index [0]				

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 , and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. Propagation conditions are set according to Annex B.0.
- 5. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.3.4.4.3.

# 6.3.3.4.4.2 Test procedure

- 1. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 2. The SS shall signal a Random Access Preamble ID via a PDCCH order to the UE and initiate a Non-contention based Random Access procedure.
- 3. The UE shall send the signalled preamble to the SS.
- 4. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.4.5-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the slot prior to the PRACH transmission, excluding a transient period of 5 μs in the end of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 5. For UE transmission ON power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.4.5-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the slot during the PRACH preamble transmission. EIRP is calculated considering both polarizations, theta and phi. For TDD, only slots consisting of only UL symbols are under test.
- 6. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table

6.3.3.2.5-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the slot following the PUSCH transmission, excluding a transient period of 5  $\mu$ s at the beginning of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.

NOTE 1: The BEAM\_SELEECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.3.3.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions:

## Table 6.3.3.4.4.3-1: RACH-ConfigCommon: PRACH measurement

Derivation Path: TS 38.508-1[5], Table 4.6.3-128			
Information Element	Value/remark	Comment	Condition
RACH-ConfigCommon::= SEQUENCE {			
rach-ConfigGeneric	RACH-ConfigGeneric		
totalNumberOfRA-Preambles	Not present		
ssb-perRACH-OccasionAndCB-PreamblesPerSSB			
CHOICE {			
one	n4		FR2
}			
groupBconfigured	Not present		
ra-ContentionResolutionTimer	sf64		
rsrp-ThresholdSSB	RSRP-Range		
rsrp-ThresholdSSB-SUL	Not present		
	RSRP-Range		SUL
prach-RootSequenceIndex CHOICE {			
1139	Set according to table		PRACH
	4.4.2-2 for the NR Cell.		Format A3
}			
msg1-SubcarrierSpacing	SubcarrierSpacing		
restrictedSetConfig	unrestrictedSet		
msg3-transformPrecoder	Not present	transform	
		precoding is	
		disabled for Msg3	
		PUSCH	
		transmission and	
		any PUSCH	
		transmission	
		scheduled with	
		DCI format 0_0	
1 }			

#### Table 6.3.3.4.4.3-2: RACH-ConfigGeneric: PRACH measurement

Derivation Path: TS 38.508-1[5], Table 4.6.3-130			
Information Element	Value/remark	Comment	Condition
RACH-ConfigGeneric ::= SEQUENCE {			
prach-ConfigurationIndex	[TBD]	Unpaired Spectrum	PRACH Format A3
msg1-FDM	one		FR2
msg1-FrequencyStart	0		
zeroCorrelationZoneConfig	15		
preambleReceivedTargetPower	[TBD]		PRACH Format A3
preambleTransMax	n7		
powerRampingStep	dB0		
ra-ResponseWindow }	sl20		

Derivation Path: TS 38.508-1[5], Table 4.6.3-169			
Information Element	Value/remark	Comment	Condition
ServingCellConfigCommonSIB ::= SEQUENCE {			
downlinkConfigCommon	DownlinkConfigCommon SIB		
uplinkConfigCommon	UplinkConfigCommonSIB		
supplementaryUplink	Not present		
	UplinkConfigCommonSIB		SUL
n-TimingAdvanceOffset	Not present		
ssb-PositionsInBurst SEQUENCE {			
inOneGroup	'1000 0000'B		
groupPresence	Not present		
}			
tdd-UL-DL-ConfigurationCommon	TDD-UL-DL- ConfigCommon		FR2_TDD
ss-PBCH-BlockPower	[TBD]		
}			

Table 6.3.3.4.4.3-3: ServingCellConfigCommonSIB: PRACH measurement

# 6.3.3.4.5 Test requirement

The requirement for the power measured in steps (3), (4) and (5) of the test procedure shall not exceed the values specified in Table 6.3.3.4.5-1.

	Channel bandwidth / Output Power [dBm] / measurement bandwidth					
	50MHz	100MHz	200MHz	400MHz		
Transmit OFF power		≤ -30+TT + R				
Transmission OFF	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
Measurement bandwidth						
Expected PRACH	FFS	FFS	FFS	FFS		
Transmission ON						
Measured power						
ON power tolerance	FFS	FFS	FFS	FFS		
FFS						
NOTE 1: Core requirement cannot be tested due to testability issue and test requirement						
includes relaxation to achieve impact from test system noise to measurement						
result = 1.0 dB (Minimum requirement + relaxation R).						
NOTE 2: Relaxation R is specified in Table 6.3.3.4.5-2.						

Table 6.3.3.4.5-1: PRACH time mask

Operating band	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n261	19.4 dB	22.4 dB	25.4 dB	28.4 dB
n260	21.5 dB	24.5 dB	27.5 dB	30.5 dB

Table 6.3.3.4.5-3: Relaxations for ON power

FFS

- 6.3.3.5 Void
- 6.3.3.6 SRS time mask

FFS

# 6.3.3.7 PUSCH-PUCCH and PUSCH-SRS time masks

No test case details are specified. Current test procedures for time masks are based on power measurement in relatively long period compared with transient period. For time masks between 2 active time slots with different power level, the test procedure can't provide enough resolution to identify non-conformant UEs. Therefore the minimum requirement is not testable.

# 6.3.3.8 Transmit power time mask for consecutive slot or long subslot transmission and short subslot transmission boundaries

No test case details are specified. Current test procedures for time masks are based on power measurement in relatively long period compared with transient period. For time masks between 2 active time slots with different power level, the test procedure can't provide enough resolution to identify non-conformant UEs. Therefore the minimum requirement is not testable.

# 6.3.3.9 Transmit power time mask for consecutive short subslot transmissions boundaries

No test case details are specified. Current test procedures for time masks are based on power measurement in relatively long period compared with transient period. For time masks between 2 active time slots with different power level, the test procedure can't provide enough resolution to identify non-conformant UEs. Therefore the minimum requirement is not testable.

# 6.3.4 Power control

# 6.3.4.1 General

The requirements on power control accuracy apply under normal conditions and are defined as a directional requirement. The requirements are verified in beam locked mode on beam peak direction.

# 6.3.4.2 Absolute power tolerance

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- Testing of extreme conditions for FR2 is FFS.
- TP analysis is FFS.
- UE transmitted power for PC 1, 2 and 4 are FFS

# 6.3.4.2.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

# 6.3.4.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

# 6.3.4.2.3 Minimum conformance requirements

The absolute power tolerance is the ability of the UE transmitter to set its initial output power to a specific value for the first sub-frame (1ms) at the start of a contiguous transmission or non-contiguous transmission with a transmission gap larger than 20 ms. The tolerance includes the channel estimation error RSRP estimate.

The minimum requirements specified in Table 6.3.4.2.3-1 apply in the power range bounded by the minimum output power as specified in sub-clause 6.3.1.3 ( $P_{min}$ ) and the maximum output power as specified in sub-clause 6.2.1.1 as minimum peak EIRP (' $P_{max}$ '). The intermediate power point ' $P_{int}$ ' is defined in table 6.3.4.2.3-2.

Table 6.3.4.2.3-1: Absolute power tolerance

Power Range	Tolerance	
$P_{int} \ge P \ge P_{min}$	± 14.0 dB	
$P_{max} \ge P > P_{int}$	± 12.0 dB	

#### Table 6.3.4.2.3-2: Intermediate power point

Power Parameter	Value
Pint	P <sub>max</sub> – 12.0 dB

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.4.2.

## 6.3.4.2.4 Test description

#### 6.3.4.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3.4.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

 Table 6.3.4.2.4.1-1: Test Configuration Table

	Initial Conditions					
Test Environment as specified in TS 38.508-1 [10]		Normal				
subclause 4.1 Test Frequencies as specified in TS 38.508-1 [10]		Mid range				
subclause		Laurat Mal Linkaat				
	nel Bandwidths as specified in TS 38.508- clause 4.3.1	Lowest, Mid, Highest				
Test SCS a	as specified in Table 5.3.5-1.	Highest				
	Test	Parameters				
	Downlink Configuration	Uplink Configuration				
Test ID	N/A for absolute power tolerance test	Modulation	RB allocation (NOTE 1)			
1 Case		DFT-s-OFDM QPSK	Outer_Full			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3.4.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.4.2.4.3.

#### 6.3.4.2.4.2 Test procedure

- 1. SS sends uplink scheduling information via PDCCH DCI format 0\_1 with TPC command 0dB for C\_RNTI to schedule the UL RMC according to Table 6.3.1.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Configure the UE transmitted output power to test point 1 in section 6.3.4.2.4.3. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP of the first subframe in the Tx beam peak direction in the measurement bandwidth specified in Table 6.3.1.5-1 and Table 6.3.1.5-2 for the specific channel bandwidth under test. EIRP test procedure is defined in Annex K. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 7. Repeat test steps 1~6 for measurement of test point 2~3. The timing of the execution between the two test points shall be larger than 20ms.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.3.4.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions:

# Table 6.3.4.2.4.3-1: PUSCH-PowerControl (Test point 1) for power class 3

Derivation Path: TS 38.508-1 [10], Table 4.3.3-91			
Information Element	Value/remark	Comment	Condition
PUSCH-PowerControl ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0-	1 entry		
PUSCH-AlphaSets)) OF SEQUENCE {			
p0	-116		50MHz
	-120		100MHz
	-122		200MHz
	-126		400MHz
alpha	alpha1		
}			
}			

## Table 6.3.4.2.4.3-2: PUSCH-PowerControl (Test point 2) for power class 3

Derivation Path: TS 38.508-1 [10], Table 4.3.3-91			
Information Element	Value/remark	Comment	Condition
PUSCH-PowerControl ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0- PUSCH-AlphaSets)) OF SEQUENCE {	1 entry		
p0	-112		50MHz
	-116		100MHz
	-118		200MHz
	-122		400MHz
alpha	alpha1		
}			
}			

Information Element	Value/remark	Comment	Condition
PUSCH-PowerControl ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0- PUSCH-AlphaSets)) OF SEQUENCE {	1 entry		
p0	-102		50MHz
	-106		100MHz
	-118		200MHz
	-112		400MHz
alpha	alpha1		
}			
}			

# Table 6.3.4.2.4.3-3: PUSCH-PowerControl (Test point 3) for power class 3

# Table 6.3.4.2.4.3-4: ServingCellConfigCommon

Information Element	Value/remark	Comment	Condition
ServingCellConfigCommon ::= SEQUENCE {			
ss-PBCH-BlockPower	1		SCS_60kHz
	4		SCS_120kH
			z
}			

Condition	Explanation
SCS_60kHz	SCS=60kHz for SS/PBCH block
SCS_120kHz	SCS=120kHz for SS/PBCH block

# 6.3.4.2.5 Test requirement

The measured EIRP in step 5 and 7 shall not to exceed the values specified in Table 6.3.4.2.5-1 to 6.3.4.2.5-3.

Table 6.3.4.2.5-1: Absolute	power tolerance: test	point 1 for power class 3

	SCS	Channel bandwidth / expected output power (dBm)			
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	8.1	7.1	8.1	N/A
power	120kHz	8.1 7.1 8.1 7.1			
Power toleran	ce	± (14+TT)dB			
Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2.1.3.					

		SCS	Channel bandwidth / expected output power (dBm)			
			50 MHz	100 MHz	200 MHz	400 MHz
Expected	Measured	60kHz	12.1	11.1	12.1	N/A
рс	ower	120kHz	12.1	11.1	12.1	11.1
P	Power tolerance ± (12+TT)dB					
Note 1: The lower power limit shall not exceed the minimum output power requirements						
defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max						
EIRP defined in sub-clause 6.2.1.3.						

	SCS	Channel bandwidth / expected output power (dBm)			
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	22.1	21.1	22.1	N/A
power	120kHz	22.1 21.1 22.1 21.1			
Power toleran	се	± (12+TT)dB			
Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2.1.3.					

 Table 6.3.4.2.5-3: Absolute power tolerance: test point 3 for power class 3

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

#### Table 6.3.4.2.5-5: Test Tolerance (Test point 2)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

# 6.3.4.3 Relative power tolerance

Editor's note: The following items are missing or incomplete:

- MU and TT not defined
- Starting power at ramp up/ramp down/alternating sub-test is TBD (6.3.4.3 MU dependent)
- Testability of test points needs further analysis, based on MU outcome

#### 6.3.4.3.1 Test purpose

To verify the ability of the UE transmitter to set its output power in a target sub-frame relatively to the power of the most recently transmitted reference sub-frame if the transmission gap between these sub-frames is less than or equal to 20 ms.

6.3.4.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.3.4.3.3 Minimum conformance requirements

The minimum requirements specified in Table 6.3.4.3.3-1 apply when the power of the target and reference sub-frames are within the power range bounded by the minimum output power as defined in sub-clause 6.3.1 and Pint as defined in sub-clause 6.3.4.3-2. The minimum requirements specified in Table 6.3.4.3-2 apply when the power of the target and reference sub-frames are within the power range bounded by Pint as defined in sub-clause 6.3.4.2 and the measured  $P_{\text{UMAX}}$  as defined in sub-clause 6.2.4.

For a test pattern that is either a monotonically increasing or monotonically decreasing power sweep over the range specified for Tables 6.3.4.3.3-1 and 6.3.4.3.3-2, 3 exceptions are allowed for each of the test patterns. For these exceptions, the power tolerance limit is a maximum of  $\pm 11.0$  dB.

Power step ∆P (Up or down) (dB)	All combinations of PUSCH and PUCCH, PUSCH/PUCCH and SRS transitions between sub- frames, PRACH (dB)			
ΔP < 2	±5.0			
2 ≤ ΔP < 3	±6.0			
3 ≤ ΔP < 4	±7.0			
4 ≤ ΔP < 10	±8.0			
10 ≤ ΔP < 15	±10.0			
15 ≤ ∆P	±11.0			
NOTE: The requirements apply with <i>ue-BeamLockFunction</i> enabled.				

Table 6.3.4.3.3-1: Relative power tolerance,  $P_{int} \ge P \ge P_{min}$ 

Power step ∆P (Up or down) (dB)	All combinations of PUSCH and PUCCH, PUSCH/PUCCH and SRS transitions between sub- frames, PRACH (dB)			
ΔP < 2	±3.0			
2 ≤ ΔP < 3	±4.0			
3 ≤ ΔP < 4	±5.0			
4 ≤ ΔP < 10	±6.0			
10 ≤ ΔP < 15	±8.0			
15 ≤ ΔP	±9.0			
NOTE 1: The requirements apply with <i>ue-BeamLockFunction</i> enabled. NOTE 2: For PUSCH to PUSCH transitions with the allocated resource blocks fixed in frequency and no transmission gaps other than those generated by downlink subframes, guard periods: for a power step $\Delta P = 1$ dB, the relative power tolerance for transmission is ± 1.0 dB.				

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.4.3.

#### 6.3.4.3.4 Test description

#### 6.3.4.3.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.3.4.3.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Initial Conditions							
Test Environment as specified in TS 38.508-1 [10]			Normal				
subclause 4							
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Low Range				
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1			100MHz				
Test SCS as	s specified in TS 38.508	-1 [10] subclause	60kHz				
4.3.1	•						
Test Parameters							
Ch BW	Downlink Co	onfiguration	Uplink Configuration				
	Modulation	<b>RB</b> Allocation	Modulation	RB allocation (NOTE 1)			
100MHz	N/A for Relative power tolerance test case		DFT-s-OFDM pi/2	See Table 6.3.4.3.5-1			
1		BPSK	See Table 6.3.4.3.5-2				
				See Table 6.3.4.3.5-3			
Note 1: The starting resource block shall be RB# 1.							

# Table 6.3.4.3.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.3.4.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.4.3.4.3

#### 6.3.4.3.4.2 Test procedure

The procedure is separated in various subtests to verify different aspects of relative power control. The power patterns of the subtests are described in figure 6.3.4.3.4.2-1 thru figure 6.3.4.3.4.2-3. The power patterns and corresponding sub frame numberings are derived from Table A.2.3-1.

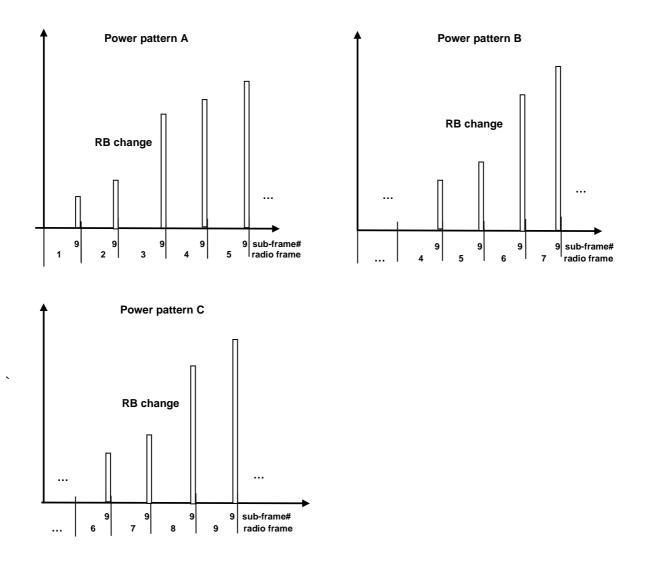


Figure 6.3.4.3.4.2-1: TDD ramping up test power patterns, SCS 60kHz

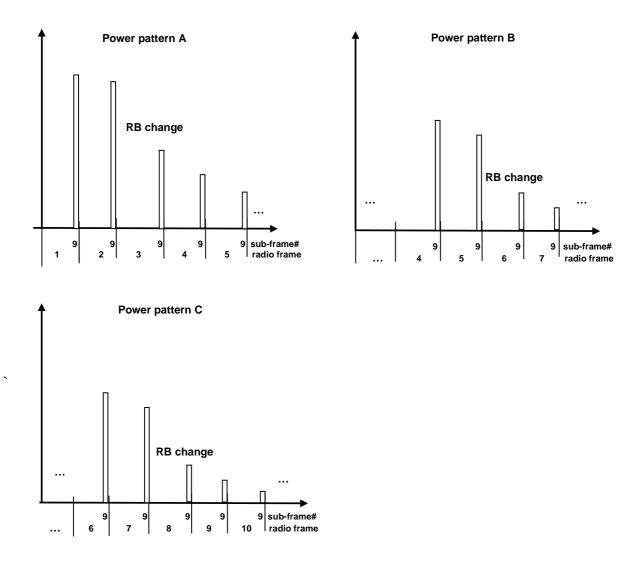
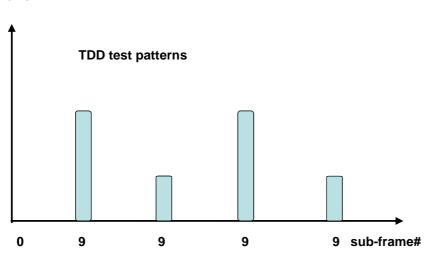


Figure 6.3.4.3.4.2-2: TDD ramping down test power patterns, SCS 60kHz

Power





- 1. Sub test: ramping up pattern
  - 1.1 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.4.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
  - 1.2 Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
  - 1.3 Send the appropriate TPC commands in the uplink scheduling information to UE until the UE EIRP measured by the test system is within the Uplink power control window, defined as +MU to +(MU + Uplink power control window size) dB of the target power level Pmin, where:
  - Pmin is the minimum output power according to Table 6.3.1.3-1.
  - MU is the test system uplink power measurement uncertainty and is specified in Table F.1.2-1 for the carrier frequency f and the channel bandwidth BW.
  - Uplink power control window size = 1dB (UE power step size) + 5dB (UE power step tolerance) = 6dB, where, the UE power step tolerance is specified in TS 38.101-2 [3], Table 6.3.4.3-1 and is 5dB for 1dB power step size.

Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.

- 1.4 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 1.5 Schedule the UE's PUSCH data transmission as described in Figure 6.3.4.3.4.2-1 (TDD) pattern A: Uplink RB allocation as defined in table 6.3.4.3.5-1. On the PDCCH format 0\_1 for the scheduling of the PUSCH the SS will transmit +1dB TPC commands over a sequence of 75 (note1) active uplink sub-framesto ensure that the UE reaches maximum power threshold. Note that the measurement need not be done continuously, provided that interruptions are whole numbers of frames, and TPC commands of 0dB are sent during the interruption.
- 1.6 Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, to verify the UE relative power control meet test requirements in 6.3.4.3.5. EIRP test procedure is defined in Annex K.1.3. EIRP is calculated considering both polarizations, theta and phi. Measurement of the power is not required in sub-frame after the mean power has exceeded the maximum power threshold. For power transients between sub-frames, transient periods of 40us between sub-frames.

frames are excluded. For ON/OFF or OFF/ON transients, transient periods of 20 us at the beginning of the sub-frames are excluded.

- 1.7 Repeat the subtest different pattern B, C to move the RB allocation change at different points in the pattern as described in Table 6.3.4.3.5-1 to force different UE power steps at various points in the power range.
- 1.8 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 2. Sub test: ramping down pattern
  - 2.1 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.4.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
  - 2.2 Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
  - 2.3 Send the appropriate TPC commands in the uplink scheduling information to UE until the UE EIRP measured by the test system is within the Uplink power control window, defined as +MU to +(MU + Uplink power control window size) dB of the target power level  $P_{UMAX}$ , where:
  - P<sub>UMAX</sub> is the maximum output power according to Table 6.2.1.1.3.3-2.
  - MU is the test system uplink power measurement uncertainty and is specified in Table F.1.2-1 for the carrier frequency f and the channel bandwidth BW.
  - Uplink power control window size = 1dB (UE power step size) + 1dB (UE power step tolerance) = 2dB, where, the UE power step tolerance is specified in TS 38.101-2 [3], Table 6.3.4.3-2 and is 1dB for 1dB power step size.

Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.

- 2.4 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 2.5. Schedule the UE's PUSCH data transmission as described in Figure 6.3.4.3.4.2-2 (TDD) pattern A: Uplink RB allocation as defined in table 6.3.4.3.5-1. On the PDCCH format 0\_1 for the scheduling of the PUSCH the SS will transmit -1dB TPC commands over a sequence of 75 (note1) active uplink sub-frames to ensure that the UE reaches minimum power threshold. Note that the measurement need not be done continuously, provided that interruptions are whole numbers of frames, and TPC commands of 0dB are sent during the interruption.
- 2.6. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, to verify the UE relative power control meet test requirements in 6.3.4.3.5. EIRP test procedure is defined in Annex K.1.3. EIRP is calculated considering both polarizations, theta and phi. Measurement of the power is not required in sub-frame after the mean power has exceeded the maximum power threshold. For power transients between sub-frame, transient periods of 40us between sub-frame are excluded. For ON/OFF or OFF/ON transients, transient periods of 20 us at the beginning of the sub-frame are excluded.
- 2.7. Repeat the subtest different pattern B, C to move the RB allocation change at different points in the pattern as described in Table 6.3.4.3.5-2/6.3.4.3.5-4/ 6.3.4.3.5-6 to force different UE power steps at various points in the power range.
- 2.8 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 3. Sub test: alternating pattern
  - 3.1 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.4.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. The initial uplink RB allocation is defined as the smaller uplink RB allocation value specified in table 6.3.4.3.4.1-1. The power level and RB allocation are reset for each sub-test.

- 3.2 Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3.3 Send the appropriate TPC commands in the uplink scheduling information to UE until the UE EIRP measured by the test system is within the Uplink power control window, defined as +MU to +(MU + Uplink power control window size) dB of the target power level 0 dBm, where:
- MU is the test system uplink power measurement uncertainty and is specified in Table F.1.2-1 for the carrier frequency f and the channel bandwidth BW.
- Uplink power control window size = 1dB (UE power step size) + 5dB (UE power step tolerance) = 6dB, where, the UE power step tolerance is specified in TS 38.101-2 [3], Table 6.3.4.3-1 and is 5dB for 1dB power step size.

Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.

- 3.4 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 3.5. Schedule the UE's PUSCH data transmission as described in Figure 6.3.5.2.4.2-3 for 5 frames with an uplink RB allocation alternating pattern as defined in table 6.3.4.3.5-3 while transmitting 0dB TPC command for PUSCH via the PDCCH.
- 3.6. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, to verify the UE relative power control meet test requirements in 6.3.4.3.5. EIRP test procedure is defined in Annex K.1.3. EIRP is calculated considering both polarizations, theta and phi. Measurement of the power is not required in sub-frame after the mean power has exceeded the maximum power threshold. For power transients between sub-frames, transient periods of 40us between sub-frames are excluded. For ON/OFF or OFF/ON transients, transient periods of 20 us at the beginning of the sub-frame are excluded.
- 3.7 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 2: These numbers of TPC commands are given as examples. The actual number of TPC commands transmitted in these steps shall be enough to ensure that the UE reaches the relevant maximum or minimum power threshold in each step, as shown in figure 6.3.4.3.4.2-1 thru 6.3.4.3.4.2-3.

#### 6.3.4.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.3.4.3.5 Test requirement

Each UE power step measured in the test procedure 6.3.4.3.4.2 should satisfy the test requirements specified in Table 6.3.4.3.5-1 thru 6.3.4.3.5-3.

For a test pattern that is either a monotonically increasing or monotonically decreasing power sweep over the range specified for Tables 6.3.4.3.3-1 and 6.3.4.3.3-2, 3 exceptions are allowed for each of the test patterns. For these exceptions, the power tolerance limit is a maximum of  $\pm$  (11.0 + TT) dB. If there is an exception in the power step caused by the RB change for all test patterns (A, B, C) then fail the UE.

Table 6.3.4.3.5-1: Test Requirements Relative Power Tolerance for Transmission, channel BW100MHz, SCS 60kHz, ramp up sub-test

Sub- test	Applicable sub-	Uplink RB allocation	TPC command	Expected power	Power step size	
ID	frames	anocation	command	step size	range (Up)	PUSCH
				(Up) ΔΡ [dB]	ΔΡ [dB]	[dB]
	Sub- frames before RB change	105RBs	TPC=+1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
1	RB change	105RBs to 128 RBs	TPC=+1dB	1.86	ΔP < 2dB	1.86 +/- (5.0 + TT) (NOTE 1) 1.86 +/- (3.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	90RBs	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
2	RB change	90RBs to 128 RBs	TPC=+1dB	2.53	2dB ≤ ΔP < 3dB	2.53 +/- (6.0 + TT) (NOTE 1) 2.53 +/- (4.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	79RBs	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
3	RB change	79RBs to 128 RBs	TPC=+1dB	3.10	3dB ≤ ΔP < 4dB	3,10 +/- (7.0 + TT) (NOTE 1) 3,10 +/- (5.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128RBs	TPC=+1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	32RBs	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
4	RB change	32RBs to 128 RBs	TPC=+1dB	7.02	4dB ≤ ΔP < 10dB	7.02 +/- (8.0 + TT) (NOTE 1) 7.02 +/- (6.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128	TPC=+1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	7RBs	TPC=+1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
5	RB change	7RBs to 128 RBs	TPC=+1dB	13.62	10dB ≤ ΔP < 15dB	13.62 +/- (10.0 + TT) (NOTE 1) 13.62 +/- (8.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128RBs	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	1RB	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
6	RB change	1RB to 128 RBs	TPC=+1dB	22.07	15dB < ∆P	22.07 +/- (11.0 + TT) (NOTE 1) 22.07 +/- (9.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 128	TPC=+1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)

NOTE 1:Applicable if Pint  $\geq P \geq Pmin$ .NOTE 2:Applicable if PUMAX  $\geq P > Pint$ .NOTE 3:Applicable if PUMAX  $\geq P \geq Pmin$ . Pmin as defined in sub-clause 6.3.1.

Table 6.3.4.3.5-2: Test Requirements Relative Power Tolerance for Transmission, channel BW100MHz, SCS 60kHz, ramp down sub-test

Sub-	Applicable	Uplink RB	TPC	Expected		
test ID	sub- frames	allocation	command	power step size	Power step size range (Down)	PUSCH
				(Down) ∆P [dB]	ΔP [dB]	[dB]
	Sub-	128RBs	TPC=-1dB			
	frames before RB change			1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
1	RB change	128RBs to 105 RBs	TPC=-1dB	1.86	ΔP < 2dB	1.86 +/- (5.0 + TT) (NOTE 1) 1.86 +/- (3.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 105	TPC=-1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	128RBs	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
2	RB change	128RBs to 90 RBs	TPC=-1dB	2.53	2dB ≤ ΔP < 3dB	2.53 +/- (6.0 + TT) (NOTE 1) 2.53 +/- (4.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 90	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	128RBs	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
3	RB change	128RBs to 79 RBs	TPC=-1dB	3.10	3dB ≤ ΔP < 4dB	3,10 +/- (7.0 + TT) (NOTE 1) 3,10 +/- (5.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 79RBs	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	128RBs	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
4	RB change	128RBs to 32 RBs	TPC=-1dB	7.02	$4dB \le \Delta P < 10dB$	7.02 +/- (8.0 + TT) (NOTE 1) 7.02 +/- (6.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 32	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	128RBs	TPC=-1dB	1	ΔP ≤ 1 dB	1 +/- (1.0 + TT)
5	RB change	128RBs to 7 RBs	TPC=-1dB	13.62	10dB ≤ ΔP < 15dB	13.62 +/- (10.0 + TT) (NOTE 1) 13.62 +/- (8.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 7RBs	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
	Sub- frames before RB change	128RB	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)
6	RB change	128RB to 1 RBs	TPC=-1dB	22.07	15dB < ∆P	22.07 +/- (11.0 + TT) (NOTE 1) 22.07 +/- (9.0 + TT) (NOTE 2)
	Sub- frames after RB change	Fixed = 1	TPC=-1dB	1	∆P ≤ 1 dB	1 +/- (1.0 + TT)

NOTE 1:	Applicable if $Pint \ge P \ge Pmin$ .
NOTE 2:	Applicable if $PUMAX \ge P > Pint$ .
NOTE 3:	Applicable if PUMAX $\geq$ P $\geq$ Pmin. Pmin as defined in sub-clause 6.3.1.

# Table 6.3.4.3.5-3: Test Requirements Relative Power Tolerance for Transmission, channel BW 100MHz, SCS 60kHz, alternating sub-test

Sub- test ID	Uplink RB allocation	TPC command	Expected power step size (Up/Down) ΔP [dB]	Power step size range (Up/Down) ΔΡ [dB]	PUSCH [dB]	
1	Alternating 105 and 128	TPC=0dB	0.86	ΔP < 2dB	0.86 +/- (5.0 + TT) (NOTE 1) 0.86 +/- (3.0 + TT) (NOTE 2)	
2	Alternating 79 and 128	TPC=0dB	2.10	2dB ≤ ΔP < 3dB	2.10 +/- (6.0 + TT) (NOTE 1) 2.10 +/- (4.0 + TT) (NOTE 2)	
3	Alternating 64 and 128	TPC=0dB	3.01	3dB ≤ ΔP < 4dB	3.01 +/- (7.0 + TT) (NOTE 1) 3.01 +/- (5.0 + TT) (NOTE 2)	
4	Alternating 32 and 128	TPC=0dB	6.02	4dB ≤ ∆P < 10dB	6.02 +/- (8.0 + TT) (NOTE 1) 6.02 +/- (6.0 + TT) (NOTE 2)	
5	Alternating 7 and 128	TPC=0dB	12.62	10dB ≤ ΔP < 15dB	12.62 +/- (10.0 + TT) (NOTE 1) 12.62 +/- (8.0 + TT) (NOTE 2)	
6	Alternating 1 and 128	TPC=0dB	21.07	15dB < ΔP	21.07 +/- (11.0 + TT) (NOTE 1) 21.07 +/- (9.0 + TT) (NOTE 2)	
NOTE 1: Applicable if Pint $\geq$ P $\geq$ Pmin.NOTE 2: Applicable if PUMAX $\geq$ P > Pint.						

NOTE 3: Applicable if  $PUMAX \ge P \ge Pmin$ . Pmin as defined in sub-clause 6.3.1.

### 6.3.4.4 Aggregate power tolerance

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- UE transmitted power for power class 1, 2 and 4 is FFS.
- Power window is FFS.

### 6.3.4.4.1 Test purpose

To verify the ability of the UE transmitter to maintain its power during non-contiguous transmissions within 21ms in response to 0 dB commands with respect to the first UE transmission and all other power control parameters as specified in 38.213 kept constant.

### 6.3.4.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.3.4.4.3 Minimum conformance requirements

The aggregate power control tolerance is the ability of the UE transmitter to maintain its power in a sub-frame (1 ms) non-contiguous transmissions within 21ms in response to 0 dB TPC commands with respect to the first UE transmission and all other power control parameters as specified in 38.213 kept constant.

The minimum requirements specified in Table 6.3.4.4.3-1 apply when the power of the target and reference sub-frames are within the power range bounded by the minimum output power as defined in sub-clause 6.3.1 and  $P_{int}$  as defined in sub-clause 6.3.4.2. The minimum requirements specified in Table 6.3.4.3-2 apply when the power of the target and reference sub-frames are within the power range bounded by Pint as defined in sub-clause 6.3.4.2 and the maximum output power as specified in sub-clause 6.2.1.

TPC command	UL channel	Aggregate power tolerance within 21ms
0 dB	PUCCH	± 5.5 dB
0 dB	PUSCH	± 5.5 dB

Table 6.3.4.4.3-1: Aggregate po	ower tolerance, $P_{int} \ge P \ge P_{min}$
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### Table 6.3.4.4.3-2: Aggregate power tolerance, $P_{max} \ge P \ge P_{int}$

TPC command	UL channel	Aggregate power tolerance within 21ms
0 dB	PUCCH	± 3.5 dB
0 dB	PUSCH	± 3.5 dB

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3.4.4

#### 6.3.4.4.4 Test description

### 6.3.4.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3.4.4.4.1-1 and table 6.3.4.4.4.1-2. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

### Table 6.3.4.4.4.1-1: Test Configuration Table: PUCCH subtest

Initial Conditions				
Test Environme subclause 4.1	ent as specified in TS 38.508-1 [10]	Normal		
Test Frequenci subclause 4.3.1	es as specified in TS 38.508-1 [10] I	Mid range		
Test Channel B	andwidths as specified in TS 38.508-1	Lowest, Mid and Highest		
[10] subclause	4.3.1			
Test SCS as sp	pecified in Table 5.3.5-1	Lowest and Highest		
	Test Parameters for	Channel Bandwidths		
Test ID Downlink Configuration		Uplink Configuration		
	N/A for aggregate power tolerance	PUCCH format = Format 1		
1	testcase	Length in OFDM symbols = 14		

### Table 6.3.4.4.4.1-2: Test Configuration Table: PUSCH subtest

		Initial Conditions	
Test Environme	ent as specified in TS 38.508-1	Normal	
[10] subclause 4.1			
	es as specified in TS 38.508-1	Mid range	
[10] subclause 4.3.1			
Test Channel B	andwidths as specified in TS	Lowest, Mid and Highest	
38.508-1 [10] subclause 4.3.1			
Test SCS as specified in Table 5.3.5-1		Lowest and Highest	
	Test Parar	neters for Channel Bandwidths	
Test ID Downlink Configuration		Uplink Configur	ation
	N/A for aggregate power	Modulation	RB allocation (NOTE 1)
1 tolerance testcase		DFT-s-OFDM QPSK	Outer_Full
NOTE 1: The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or T			
6.1-2	2 for PC1.		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3.4.4.1-1 (for PUCCH subtest) and Table 6.3.4.2.4.1-2 (for PUSCH subtest).
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3.4.2.4.3.

#### 6.3.4.4.2 Test procedure

The procedure is separated in two subtests to verify PUCCH and PUSCH aggregate power control tolerance respectively. The uplink transmission patterns are described in figure 6.3.4.4.2-1.

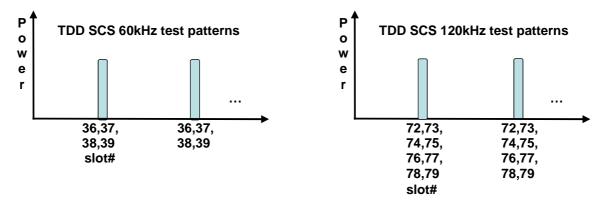


Figure 6.3.4.4.4.2-1: Test uplink transmission

#### 1. PUCCH subtest:

- 1.1. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1.
- 1.2. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 1.3. The SS transmits PDSCH via PDCCH DCI format 0\_1 for C\_RNTI to transmit the DL RMC according to Table 6.3.4.4.1-1. The SS sends downlink MAC padding bits on the DL RMC. The transmission of PDSCH will make the UE send uplink ACK/NACK using PUCCH. Send uplink power control commands for PUCCH to the UE using 1dB power step size to ensure that the UE output power measured by the test system is within  $P_W$  of the target power level specified in Table 6.3.4.4.2-1 according to the power class with power ID = 1.  $P_W$  is the power window according to Table 6.3.4.4.2-2 for the carrier frequency f and the channel bandwidth BW.
- 1.4. Every 10 sub-frames (10ms) transmit to the UE downlink PDSCH MAC padding bits as well as 0 dB TPC command for PUCCH via the PDCCH to make the UE transmit ACK/NACK on the PUCCH for 1 sub-frame (1ms). The downlink transmission is scheduled in the appropriate slots to make the UE transmit PUCCH as described in figure 6.3.4.4.4.2-1.
- 1.5. Measure the UE EIRP of 3 consecutive PUCCH transmissions in the Tx beam peak direction of in the measurement bandwidth specified in Table 6.3.1.5-1 and Table 6.3.1.5-2 to verify the UE transmitted PUCCH power is maintained within 21ms. EIRP test procedure is defined in Annex K. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 1.6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

1.7. Repeat test steps 1.2 to 1.6 for measurement for power ID = 2 in Table 6.3.4.4.2-1.

- 2. PUSCH subtest:
- 2.1. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1.
- 2.2. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 2.3. The SS sends uplink scheduling information via PDCCH DCI format  $0_1$  for C\_RNTI to schedule the PUSCH. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Send uplink power control commands for PUSCH to the UE using 1dB power step size to ensure that the UE output power measured by the test system is within P<sub>w</sub> of the target power level specified in Table 6.3.4.4.2-1 according to the power class with power ID = 1. P<sub>w</sub> is the power window according to Table 6.3.4.4.2-2 for the carrier frequency f and the channel bandwidth BW.
- 2.4. Every 10 sub-frames (10ms) schedule the UE's PUSCH data transmission for 1 sub-frame (1ms)and transmit 0 dB TPC command for PUSCH via the PDCCH to make the UE transmit PUSCH. The uplink transmission patterns are described in figure 6.3.4.4.2-1.
- 2.5. Measure the UE EIRP of 3 consecutive PUSCH transmissions in the Tx beam peak direction of in the measurement bandwidth specified in Table 6.3.1.5-1 and Table 6.3.1.5-2 to verify the UE transmitted PUSCH power is maintained within 21ms. EIRP test procedure is defined in Annex K. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 2.6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 2.7. Repeat test steps 2.2 to 2.6 for measurement for power ID = 2 in Table 6.3.4.4.2-1.

Power ID	Unit	power class 1	power class 2	power class 3	power class 4
1	dBm	TBD	TBD	0	TBD
2	dBm	TBD	TBD	15	TBD

Table 6.3.4.4.4.2-1: Parameters for Aggregate power tolerance

### Table 6.3.4.4.4.2-2: Power Window (dB) for Aggregate Power tolerance for PUSCH and PUCCH

FFS

### 6.3.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

### 6.3.4.4.5 Test requirement

The requirement for the power measurements made in step (1.5) and (2.5) of the test procedure shall not exceed the values specified in Table 6.3.4.4.5-1 and Table 6.3.4.4.5-2. The power measurement period shall be 1 sub-frame (1ms).

TPC command	UL channel	Test requirement measured power	
0 dB PUCCH		Given 3 power measurements in the pattern, the $2^{nd}$ , and later measurements shall be within ± 5.5+TTdB of the $1^{st}$	
		measurement.	
0 dB PUSCH		Given 3 power measurements in the pattern, the 2 <sup>nd</sup> , and later measurements shall be within ± 5.5+TTdB of the 1 <sup>st</sup>	
	measure		
	Note 1: TT for each duplex, Sub-Carrier Spacing, frequency and channel bandwidth is specified ir		
Table 6.3.4.4.5-3.			

TPC command	UL channel	Test requirement measured power
0 dB	PUCCH	Given 3 power measurements in the pattern, the 2 <sup>nd</sup> , and later measurements shall be within ± 3.5+TTdB of the 1 <sup>st</sup> measurement.
0 dB	PUSCH	Given 3 power measurements in the pattern, the 2 <sup>nd</sup> , and later measurements shall be within ± 3.5+TTdB of the 1 <sup>st</sup> measurement.
Note 1: TT for each duplex, Sub-Carrier Spacing, frequency and channel bandwidth is specified in Table 6.3.4.4.5-4.		

Table 6.3.4.4.5-2: Power control tolerance ( $P_{max} \ge P > P_{int}$ )

Table 6.3.4.4.5-3:	<b>Test Tolerance</b>	$(\mathbf{P}_{int} \geq \mathbf{P} \geq \mathbf{P}_{min})$
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Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

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Table 6.3.4.4.5-4: Test Tolerance	$(P_{max} \ge P > P_{int})$
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Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	FFS	FFS

# 6.3A Output power dynamics for CA

## 6.3A.1 Minimum output power for CA

FFS

### 6.3A.1.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the minimum controlled output power of the UE is defined as the transmit power of the UE per component carrier, i.e., EIRP in the channel bandwidth of each component carrier for all transmit bandwidth configurations (resource blocks), when the power on both component carriers are set to a minimum value.

The minimum output power is defined as the mean power in at least one subframe (1ms).

The minimum output power shall not exceed the values specified in Table 6.3A.1.0-1 and 6.3.A.1.0-2 for each operating band supported. The minimum power is verified in beam locked mode with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4	47.58
	100	4	95.16
	200	4	190.20
	400	4	380.28

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13	47.58
[	100	-13	95.16
Ī	200	-13	190.20
Ī	400	-13	380.28
NOTE 1: n260 is not applie	ed for power class 2.		

Table 6.3A.1.0-2: Minimum output power for CA for power class 2, 3 and 4

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3A.1.

### 6.3A.1.1 Minimum output power for CA (2UL CA)

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.1.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that support intra-band contiguous 2UL CA.

### 6.3A.1.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.1.4 Test description

#### 6.3A.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR CA configuration specified in clause 5.5A.1-1. All of these configurations shall be tested with applicable test parameters for each CA configuration, and are shown in table 6.3A.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

			Default C	Conditions		
	nvironment as use 4.1	s specified in TS 38	3.508-1 [10]	Normal		
subcla classe physic	use [4.3.1.2.3 s, and PCC a al frequencies	s specified in TS 38 ] for different CA banched nd SCCs are mapp s according to Table	andwidth ed onto e 6.1-2.	Low and High ra	ange	
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration				
Test SCS as specified in Table 5.3.5-1.			Highest			
	Test Parameters					
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation
1	PCC	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full
	SCC	Delault	Delault	N/A	DFT-s-OFDM QPSK	Outer_Full
NOTE	1: The spec 6.1-2 for	•	each RB allocatio	on is defined in Ta	ble 6.1-1 for PC2, P	C3 and PC4 or Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3A.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3A.1.1.4.3.

### 6.3A.1.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.3A.1.1.4.3
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [TBD], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.2).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3A.1.1.4.1-1 on both PCC and SCC. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "down" commands in every uplink scheduling information to the UE; allow at least 200ms starting from the first TPC command in this step to ensure that the UE transmits at its minimum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.

- 8. Measure UE EIRP of each component carrier in the Tx beam peak direction in the measurement bandwidth specified in Table 6.3A.1.1.5-1 for the specific channel bandwidth under test. EIRP test procedure is defined in Annex K. The measuring duration is at least one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELEECT\_WAIT\_TIME default value is defined in Annex K.1.1.

6.3A.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.1.4.3-1: PUSCH-Config

Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.1.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2.

### Table 6.3A.1.1.5-1: Minimum output power for 2UL CA for power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

#### Table 6.3A.1.1.5-2: Minimum output power for 2UL CA for power class 2, 3 and 4

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
	200	-13+TT	190.20
	400	-13+TT	380.28

NOTE 1: n260 is not applied for power class 2.

### Table 6.3A.1.1.5-3: Test Tolerance for Minimum output power for 2UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### Table 6.3A.1.1.5-4: Test Tolerance for Minimum output power for 2UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### 6.3A.1.2 Minimum output power for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.

- The testability of this test case is pending further analysis on relaxation of the requirement.
  - The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.2.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

### 6.3A.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.2.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1  $\rightarrow$  use Table 6.3A.1.2.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.2.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2  $\rightarrow$  use Table 6.3A.1.2.5-1 and 6.3A.1.2.5-2.

### Table 6.3A.1.2.4.1-1: Test Configuration Table for 3UL CA

	Default Conditions					
Test El subcla		specified in TS 38	5.508-1 [10]	Normal		
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Low and High range			
5.5A.1 Config	Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.			Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration		
		d in Table 5.3.5-1.		Highest		
			Test Par	ameters		
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation
	PCC				DFT-s-OFDM QPSK	Outer_Full
1	SCC1	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full
	SCC2 DFT-s-OFDM QPSK Outer_Ful					Outer_Full
NOTE	1: The specif 6.1-2 for P		each RB allocatior	n is defined in Tab	le 6.1-1 for PC2, PC	C3 and PC4 or Table

### 6.3A.1.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.2.4.3-1: PUSCH-Config

Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

#### 6.3A.1.2.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.2.5-1 and 6.3A.1.2.5-2.

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

### Table 6.3A.1.2.5-2: Minimum output power for 3UL CA for power class 2, 3 and 4

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
	200	-13+TT	190.20
	400	-13+TT	380.28
NOTE 1: n260 is not applie	ed for power class 2	·	·

NOTE 1: n260 is not applied for power class 2.

#### Table 6.3A.1.2.5-3: Test Tolerance for Minimum output power for 3UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

#### Table 6.3A.1.2.5-4: Test Tolerance for Minimum output power for 3UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

#### 6.3A.1.3 Minimum output power for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS. \_
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

#### 6.3A.1.3.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

### 6.3A.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.3.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1  $\rightarrow$  use Table 6.3A.1.3.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.3.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2  $\rightarrow$  use Table 6.3A.1.3.5-1 and 6.3A.1.3.5-2.

### Table 6.3A.1.3.4.1-1: Test Configuration Table for 3UL CA

Default Conditions							
	Test Environment as specified in TS 38.508-1 [10]						
00.00.0	use 4.1						
	Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth				ange		
			apped onto physical				
		ing to Table 6.1-					
			cified in subclause	Lowest addreda	ted BW of the CA c	onfiguration	
		and 5.5A.2-2 for			ated BW of the CA		
		s bandwidth con				g	
suppoi	rted by the U	E.					
Test S	Test SCS as specified in Table 5.3.5-1.			Highest			
			Test Par		1		
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation	
	PCC		Default		DFT-s-OFDM QPSK	Outer_Full	
4	SCC1	Default			DFT-s-OFDM QPSK	Outer_Full	
1	SCC2	Default		N/A	DFT-s-OFDM QPSK	Outer_Full	
	SCC3				DFT-s-OFDM QPSK	Outer_Full	
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

### 6.3A.1.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.3.4.3-1: PUSCH-Config

Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.3.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.3.5-1 and 6.3A.1.3.5-2.

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

Table 6.3A.1.3.5-1: Minimum output power for 3UL CA for power class 1

### Table 6.3A.1.3.5-2: Minimum output power for 3UL CA for power class 2, 3 and 4

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
Γ	100	-13+TT	95.16
Γ	200	-13+TT	190.20
F	400	-13+TT	380.28

### Table 6.3A.1.3.5-3: Test Tolerance for Minimum output power for 4UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### Table 6.3A.1.3.5-4: Test Tolerance for Minimum output power for 4UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### 6.3A.1.4 Minimum output power for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.4.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

### 6.3A.1.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.4.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1  $\rightarrow$  use Table 6.3A.1.4.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.4.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2  $\rightarrow$  use Table 6.3A.1.4.5-1 and 6.3A.1.4.5-2.

### Table 6.3A.1.4.4.1-1: Test Configuration Table for 5UL CA

	Default Conditions					
	Test Environment as specified in TS 38.508-1 [10]					
subclause 4.1						
		s specified in TS		Low and High ra	ange	
		3] for different C/				
			apped onto physical			
		ng to Table 6.1-2				
			cified in subclause		ted BW of the CA c	
		and 5.5A.2-2 for		Highest aggrega	ated BW of the CA	configuration
•		s bandwidth con	nbination sets			
	rted by the U					
Test S	CS as specif	ied in Table 5.3.		Highest		
	1	1	Test Par		1	
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation
	PCC				DFT-s-OFDM QPSK	Outer_Full
		{			DFT-s-OFDM	
	SCC1				QPSK	Outer_Full
1	SCC2	Default	Default	N/A	DFT-s-OFDM	Outer Full
1	0002	Delault	Delault	11/7	QPSK	
	SCC3				DFT-s-OFDM	Outer_Full
					QPSK	
	SCC4				DFT-s-OFDM QPSK	Outer_Full
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

### 6.3A.1.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.4.4.3-1: PUSCH-Config

Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.4.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.4.5-1 and 6.3A.1.4.5-2.

### Table 6.3A.1.4.5-1: Minimum output power for 5UL CA for power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
Γ	200	-13+TT	190.20
	400	-13+TT	380.28

### Table 6.3A.1.4.5-2: Minimum output power for 5UL CA for power class 2, 3 and 4

### Table 6.3A.1.4.5-3: Test Tolerance for Minimum output power for 5UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### Table 6.3A.1.4.5-4: Test Tolerance for Minimum output power for 5UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### 6.3A.1.5 Minimum output power for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.5.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

### 6.3A.1.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.5.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1 → use Table 6.3A.1.5.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.5.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2 → use Table 6.3A.1.5.5-1 and 6.3A.1.5.5-2.

Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause 4.1		Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.		Low and High range				
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration				
Test S	Test SCS as specified in Table 5.3.5-1.			Highest ameters		
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation
	PCC				DFT-s-OFDM QPSK	Outer_Full
	SCC1				DFT-s-OFDM QPSK	Outer_Full
1	SCC2		Default	N/A	DFT-s-OFDM QPSK	Outer_Full
1	SCC3	Default		IN/A	DFT-s-OFDM QPSK	Outer_Full
	SCC4				DFT-s-OFDM QPSK	Outer_Full
	SCC5				DFT-s-OFDM QPSK	Outer_Full
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

### 6.3A.1.5.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.5.4.3-1: PUSCH-Config

Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.5.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.5.5-1 and 6.3A.1.5.5-2.

### Table 6.3A.1.5.5-1: Minimum output power for 6UL CA for power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

(MHz)	(dBm)	(MHz)
50	-13+TT	47.58
100	-13+TT	95.16
200	-13+TT	190.20
400	-13+TT	380.28
	50 100 200	50         -13+TT           100         -13+TT           200         -13+TT           400         -13+TT

### Table 6.3A.1.5.5-2: Minimum output power for 6UL CA for power class 2, 3 and 4

### Table 6.3A.1.5.5-3: Test Tolerance for Minimum output power for 6UL CA for Power class 1

Test Metric	FR2a	FR2b	
Quiet Zone size ≤ 30 cm	FFS	FFS	

### Table 6.3A.1.5.5-4: Test Tolerance for Minimum output power for 6UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### 6.3A.1.6 Minimum output power for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.6.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

### 6.3A.1.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.6.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1 → use Table 6.3A.1.6.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.6.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2 → use Table 6.3A.1.6.5-1 and 6.3A.1.6.5-2.

			Default Co	onditions			
Test Environment as specified in TS 38.508-1 [10] subclause 4.1		Normal					
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.		Low and High range					
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration					
Test S	CS as specifi	ied in Table 5.3.	5-1. Test Par	Highest			
Test ID	сс	ChBw(MHz)	Test frequency	DL RB JL RB UL Modulation UL RB allocat			
	PCC				DFT-s-OFDM QPSK	Outer_Full	
	SCC1				DFT-s-OFDM QPSK	Outer_Full	
	SCC2				DFT-s-OFDM QPSK	Outer_Full	
1	SCC3	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full	
	SCC4					DFT-s-OFDM QPSK	Outer_Full
	SCC5					DFT-s-OFDM QPSK	Outer_Full
	SCC6				DFT-s-OFDM QPSK	Outer_Full	
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.							

### 6.3A.1.6.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.6.4.3-1: PUSCH-Config

### Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.6.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.6.5-1 and 6.3A.1.6.5-2.

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
	200	-13+TT	190.20
	400	-13+TT	380.28
NOTE 1: n260 is not applie	ed for power class 2.		

### Table 6.3A.1.6.5-2: Minimum output power for 7UL CA for power class 2, 3 and 4

### Table 6.3A.1.6.5-3: Test Tolerance for Minimum output power for 7UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### Table 6.3A.1.6.5-4: Test Tolerance for Minimum output power for 7UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### 6.3A.1.7 Minimum output power for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- The testability of this test case is pending further analysis on relaxation of the requirement.
- The test configuration would be revisited when testability issue is concluded.
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.3A.1.7.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power on each component carrier is set to a minimum value.

### 6.3A.1.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

### 6.3A.1.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.1.0.

### 6.3A.1.7.4 Test description

Same as in clause 6.3A.1.1.4 with following exceptions:

- Instead of Table 6.3A.1.1.4.1-1 → use Table 6.3A.1.7.4.1-1.
- Instead of clause 6.3A.1.1.4.3  $\rightarrow$  use clause 6.3A.1.7.4.3.
- Instead of Table 6.3A.1.1.5-1 and 6.3A.1.1.5-2 → use Table 6.3A.1.7.5-1 and 6.3A.1.7.5-2.

			Default Co	onditions			
Test E subcla		s specified in TS	38.508-1 [10]	Normal			
Test F	requencies a	s specified in TS	38.508-1 [10]	Low and High ra	ange		
		3] for different C.		_			
			apped onto physical				
		ng to Table 6.1-					
			cified in subclause		ted BW of the CA c		
		and 5.5A.2-2 for		Highest aggrega	ated BW of the CA	configuration	
	ted by the UI	s bandwidth cor	noination sets				
		∟. ied in Table 5.3.	5-1	Highest			
10000			Test Par				
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation	
	PCC				DFT-s-OFDM QPSK	Outer_Full	
	SCC1				DFT-s-OFDM QPSK	Outer_Full	
	SCC2				DFT-s-OFDM QPSK	Outer_Full	
1	SCC3	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full	
1	SCC4	Delault	Delauit	IN/A	DFT-s-OFDM QPSK	Outer_Full	
	SCC5				DFT-s-OFDM QPSK	Outer_Full	
	SCC6					DFT-s-OFDM QPSK	Outer_Full
	SCC7				DFT-s-OFDM QPSK	Outer_Full	
NOTE	1: The spec 6.1-2 for		n of each RB allocation	n is defined in Tab	le 6.1-1 for PC2, PC	C3 and PC4 or Table	

### 6.3A.1.7.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exception.

### Table 6.3A.1.7.4.3-1: PUSCH-Config

### Derivation Path: TS 38.508-1 [10], Table 4.6.3-118 with condition TRANSFORM\_PRECODER\_ENABLED

### 6.3A.1.7.5 Test requirement

For each component carrier, the minimum EIRP shall not exceed the values specified in Table 6.3A.1.7.5-1 and 6.3A.1.7.5-2.

Table 6.3A.1.7.5-1: Minimum out	put power for 8UL CA for	power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
	200	-13+TT	190.20
Γ	400	-13+TT	380.28

 Table 6.3A.1.7.5-2: Minimum output power for 8UL CA for power class 2, 3 and 4

### Table 6.3A.1.7.5-3: Test Tolerance for Minimum output power for 8UL CA for Power class 1

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

### Table 6.3A.1.7.5-4: Test Tolerance for Minimum output power for 8UL CA for Power class 2, 3 and 4

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

## 6.3A.2 Transmit OFF power for CA

### 6.3A.2.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the transmit OFF power is defined as the TRP in the channel bandwidth per component carrier when the transmitter is OFF. The transmitter is considered OFF when the UE is not allowed to transmit or during periods when the UE is not transmitting a sub-frame. During DTX and measurements gaps, the transmitter is not considered OFF.

The transmit OFF power shall not exceed the values specified in Table 6.3A.2.0-1 for each operating band supported.

### Table 6.3A.2.0-1: Transmit OFF power for CA

Operating band	Channel bandwidth / Transmit OFF power (dBm) / measurement bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n260, n261	-35	-35	-35	-35
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz

### 6.3A.2.1 Transmit OFF power for CA (2UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- For PC3, the testability of this test case is pending further analysis on relaxation of the requirement for other than Band n257.
- For PC3, Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties, Test Tolerances and testability limit analysis is TBD for PC1/2/4.

### 6.3A.2.1.1 Test purpose

To verify that the UE transmit OFF power is lower than the value specified in the test requirement.

6.3A.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

### 6.3A.2.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.2.0.

- 6.3A.2.1.4 Test description
- 6.3A.2.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.3A.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

		Initia	I Conditions		
Test Enviro	nment as specified in 4.1	TS 38.508-1 [10]	Normal		
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Low range, Mid range, High range		
Test Chanr 1 [10] subc	nel Bandwidths as spe lause 4.3.1	cified in TS 38.508-	Highest aggregated BW of the CA configuration		
Test SCS a	as specified in Table 5	.3.5-1.	Highest		
		Test	Parameters		
	Downlink Co	onfiguration	Uplink Configuration		
Test ID	Modulation	RB allocation	Modulation	RB allocation	
1	N/A	0	N/A	0	

#### Table 6.3A.2.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.3A.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3A.2.1.4.3

### 6.3A.2.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels
- 2. The SS shall configure SCC as per TS 38.508-1 [10] subclause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in subclause 6.3A.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE) for the UE Tx beam selection to complete.
- 5. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.

6. Measure UE TRP for each component carrier for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.3A.2.1.5-1. Total radiated power is measured according to TRP measurement procedure defined in Annex K. TRP is calculated considering both polarizations, theta and phi.

NOTE : The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

### 6.3A.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.3A.2.1.5 Test Requirements

The requirement for the transmit OFF power shall not exceed the values specified in Table 6.3.2.5-1.

Operating band	Channel bandwidth / Transmit OFF power (dBm) / measurement bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
n257 <sup>2</sup>	-35+21.4	-35+24.4	-35+27.4	-35+30.4		
	47.52 MHz	95.04 MHz	190.08 MHz	380.16 MHz		
n258, n261	-35+[21.4]	-35+[24.4]	-35+[27.4]	-35+[30.4]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
n260	-35+[24.1]	-35+[27.1]	-35+[30.1]	-35+[33.1]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
NOTE 1: Core requirement cannot be tested due to testability issue and test requirement includes relaxation to achieve SNR = [10] dB (Minimum requirement + relaxation).						
NOTE2: Relaxed n257 tes	t requirement is testa	able for PC3.				

### Table 6.3A.2.1.5-1: Transmit OFF power

### 6.3A.2.2 Transmit OFF power for CA (3UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- For PC3, tThe testability of this test case is pending further analysis on relaxation of the requirement for other than Band n257.
- For PC3, Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties, Test Tolerances and testability limit analysis is TBD for PC1/2/4.

### 6.3A.2.2.1 Test purpose

To verify that the UE transmit OFF power is lower than the value specified in the test requirement.

6.3A.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

6.3A.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.2.0.

### 6.3A.2.2.4 Test description

Same as in clause 6.3A.2.1.4 with following exceptions:

- Instead of Table 6.3A.2.1.4.1-1  $\rightarrow$  use Table 6.3A.2.2.4.1-1.

- Instead of clause  $6.3A.2.1.4.3 \rightarrow$  use clause 6.3A.2.2.4.3.
- Instead of Table 6.3A.2.1.5-1  $\rightarrow$  use Table 6.3A.2.2.5-1.

### Table 6.3A.2.2.4.1-1: Test Configuration Table

	Initial Conditions					
Test Environment as specified in TS 38.508-1 [10]			Normal			
subclause 4.1 Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Low range, Mid range, High range			
Test Channel Bandwidths as specified in TS 38.508- 1 [10] subclause 4.3.1			Highest aggregated BW of the CA configuration			
Test SCS a	as specified in Table 5	.3.5-1.	Highest			
	•	Test	Parameters			
	Downlink Co	onfiguration	Upl	ink Configuration		
Test ID	Modulation	RB allocation	Modulation	RB allocation		
1	N/A	0	N/A	0		

### 6.3A.2.2.5 Test Requirements

The requirement for the transmit OFF power shall not exceed the values specified in Table 6.3.2.5-1.

Operating band	Channel bandwidth / Transmit OFF power (dBm) / measurement bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
n257 <sup>2</sup>	-35+21.4	-35+24.4	-35+27.4	-35+30.4		
	47.52 MHz	95.04 MHz	190.08 MHz	380.16 MHz		
n258, n261	-35+[21.4]	-35+[24.4]	-35+[27.4]	-35+[30.4]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
n260	-35+[24.1]	-35+[27.1]	-35+[30.1]	-35+[33.1]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
NOTE 1: Core requirement cannot be tested due to testability issue and test requirement includes						
relaxation to achieve SNR = [10] dB (Minimum requirement + relaxation).						
NOTE2: Relaxed n257 test r	equirement is testa	ble for PC3.				

### Table 6.3A.2.2.5-1: Transmit OFF power

### 6.3A.2.3 Transmit OFF power for CA (4UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- For PC3, the testability of this test case is pending further analysis on relaxation of the requirement for other than Band n257.
- For PC3, Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties, Test Tolerances and testability limit analysis is TBD for PC1/2/4.

### 6.3A.2.3.1 Test purpose

To verify that the UE transmit OFF power is lower than the value specified in the test requirement.

#### 6.3A.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.3A.2.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.2.0.

### 6.3A.2.3.4 Test description

Same as in clause 6.3A.2.1.4 with following exceptions:

- Instead of Table 6.3A.2.1.4.1-1  $\rightarrow$  use Table 6.3A.2.3.4.1-1.
- Instead of clause  $6.3A.2.1.4.3 \rightarrow$  use clause 6.3A.2.3.4.3.
- Instead of Table 6.3A.2.1.5-1 $\rightarrow$  use Table 6.3A.2.3.5-1.

### Table 6.3A.2.3.4.1-1: Test Configuration Table

	Initial Conditions					
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Low range, Mid range, High range			
	nel Bandwidths as spe lause 4.3.1	ecified in TS 38.508-	Highest aggregated BW of the CA configuration			
Test SCS a	as specified in Table 5	5.3.5-1.	Highest			
		Test	Parameters			
	Downlink Co	onfiguration	Uplink Configuration			
Test ID	Modulation	RB allocation	Modulation	RB allocation		
1	N/A	0	N/A	0		

### 6.3A.2.3.5 Test Requirements

The requirement for the transmit OFF power shall not exceed the values specified in Table 6.3.2.5-1.

On emotion of hear d	Oh an mal han d	uidde / Teanandi C				
Operating band	Channel bandy		)FF power (dBm) /	measurement		
		band	width			
	50 MHz	100 MHz	200 MHz	400 MHz		
n257 <sup>2</sup>	-35+21.4	-35+24.4	-35+27.4	-35+30.4		
	47.52 MHz	95.04 MHz	190.08 MHz	380.16 MHz		
n258, n261	-35+[21.4]	-35+[24.4]	-35+[27.4]	-35+[30.4]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
n260	-35+[24.1]	-35+[27.1]	-35+[30.1]	-35+[33.1]		
	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		
NOTE 1: Core requirement of	E 1: Core requirement cannot be tested due to testability issue and test requirement includes					
relaxation to achiev	relaxation to achieve SNR = [10] dB (Minimum requirement + relaxation).					
NOTE2: Relaxed n257 test			,			

### Table 6.3A.2.3.5-1: Transmit OFF power

# 6.3A.3 Transmit ON/OFF time mask for CA

### 6.3A.3.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the general output power ON/OFF time mask specified in subclause 6.3.3.2 is applicable for each component carrier during the ON power period and the transient periods. The OFF period as specified in subclause 6.3.3.2 shall only be applicable for each component carrier when all the component carriers are OFF.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3A.1.

### 6.3A.3.1 Transmit ON/OFF time mask for CA (2UL CA)

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.

- Test requirement of ON power is FFS.
- Testability of OFF power needs further study.
- The method of setting UE transmitted power is FFS.
- TP analysis is FFS
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

### 6.3A.3.1.1 Test purpose

To verify that the general ON/OFF time mask for CA meets the requirements given in 6.3A.3.1.5. Transmission of the wrong power increases interference to other channels, or increases transmission errors in the uplink channel.

#### 6.3A.3.1.2 Test applicability

The requirements of this test apply to all types of NR UE release 15 and forward supporting 2UL CA.

### 6.3A.3.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.3.0.

6.3A.3.1.4 Test description

#### 6.3A.3.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.2A.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 6.3A.3.1.4.1-1: Intra-band Contiguous UL CA Test Configuration Table

	Default Conditions						
		t as specifi	ed in TS 38.508-1	[10]	FFS		
	ause [4.1]						
Test F	requencies	as specifie	ed in TS 38.508-1	[10]	FFS		
subcla	ause [4.3.1.)	2.3] for diff	erent CA bandwidt	th classes			
			g (N <sub>RB_agg</sub> ) as spec		FFS		
Table	5.5A.1-1, 5	.5A.2-1 and	d 5.5A.2-2 for the	CA			
			idth combination s	sets			
suppo	orted by the	UE					
Test S	SCS as spe	cified in Ta	ble 5.3.5-1		FFS		
				Test Para	ameters		
Test	CC	Band	ChBw(MHz)	Test	DL RB	UL Modulation	UL RB
ID				frequency	allocation		allocation
Def	Default Test Settings for a CA_XG, CA_nXO Configuration (Cumulative aggregated BWchannel < 400MHz)					nnel < 400MHz)	
4							
					]		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.

- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.3A.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.2A.2.1.4.3.

6.3A.3.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels
- 2. The SS shall configure SCC as per TS 38.508-1 [10] subclause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in subclause 6.3A.3.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3A.3.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 7. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction for each component carrier in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-1. EIRP test procedure is defined in Annex K. The period of the measurement shall be the slot prior to the PUSCH transmission, excluding a transient period of 5 μs in the end of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 8. For UE transmission ON power, measure UE EIRP in the Tx beam peak direction for each component carrier in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-2. EIRP test procedure is defined in Annex K. The period of the measurement shall be one slot with PUSCH transmission. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 9. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction for each component carrier in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3.3.2.5-1. EIRP test procedure is defined in Annex K. The period of the measurement shall be the slot following the PUSCH transmission, excluding a transient period of 5 µs at the beginning of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 10. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 2: When switching to DFT-s-OFDM waveform, as specified in the test configuration Table 6.3A.3.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

### 6.3A.3.1.4.3 Message contents

Message contents are according to TS 36.508 [7] clause 4.6 with the following exceptions:

Derivation Path: TS 38.508-1[5], Table 4.6.3-119			
Information Element	Value/remark	Comment	Condition
PUSCH-ConfigCommon ::= SEQUENCE {			
p0-NominalWithGrant	-106		
}			

### Table 6.3A.3.1.4.3-1: PUSCH-ConfigCommon

### 6.3A.3.1.5 Test requirements

The requirement for the power measured in steps (3), (4) and (5) of the test procedure shall not exceed the values specified in Table 6.3.3.4.5-1.

### Table 6.3.3.2.5-1: Test requirement of OFF power of General ON/OFF time mask for 2UL CA

	Channel bandwidth / minimum output power / measurement bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
Transmit OFF power	≤ -30+TT dBm					
Transmission OFF Measurement bandwidth	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz		

### Table 6.3.3.2.5-2: Test requirement of ON power of General ON/OFF time mask for 2UL CA

	SCS	Channel band	Channel bandwidth / minimum output power / measurement bandwidth				
	[kHz]	50 MHz	100 MHz	200 MHz	400 MHz		
Expected Transmission ON	60	FFS	FFS	FFS	FFS		
Measured power for CP-OFDM	120	FFS	FFS	FFS	FFS		
Expected Transmission ON	60	FFS	FFS	FFS	FFS		
Measured power for DFT-s-OFDM	120	FFS	FFS	FFS	FFS		

### Table 6.3.3.2.5-3: Test Tolerance for OFF power

FFS

### Table 6.3.3.2.5-4: Test Tolerance for ON power

FFS

### 6.3A.4 Power control for CA

### 6.3A.4.1 General

The requirements in this section apply to a UE when it has at least one of UL or DL configured for CA operation. The requirements on power control accuracy in CA operation apply under normal conditions and are defined as a directional requirement. The requirements are verified in beam locked mode on beam peak direction. The requirements apply for one single PUCCH, PUSCH or SRS transmission of contiguous PRB allocation per configured UL CC with power setting in accordance with Clause 7.1 of [22]

### 6.3A.4.2 Absolute power tolerance for CA

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are proposed and put in brackets for further investigation.

### 6.3A.4.2.0 Minimum conformance requirements

The absolute power tolerance is the ability of the UE transmitter to set its initial output power to a specific value for the first sub-frame at the start of a contiguous transmission or non-contiguous transmission with a transmission gap on each active component carriers larger than 20 ms. For SRS switching, the absolute power tolerance is the ability of the UE transmitter to set its initial output power to a specific value for the first sub-frame at the start of a contiguous transmission with a transmission or non-contiguous transmission or non-contiguous transmission or non-contiguous transmission with a transmission gap on component carriers (to which SRS switching occurs) larger than 20 ms. The requirement can be tested by time aligning any transmission gaps on the component carriers. For intra-band contiguous CA, the absolute power control tolerance per configured UL CC is given in Tables 6.3.4.2.3-1 and 6.3.4.2.3-2.

### 6.3A.4.2.1 Absolute power tolerance for CA (2UL CA)

### 6.3A.4.2.1.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

### 6.3A.4.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA and 2DL CA.

### 6.3A.4.2.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.1.4 Test description

### 6.3A.4.2.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidth and subcarrier spacing based on NR CA configurations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA combination and subcarrier spacing, are shown in Table 6.3A.4.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Low and High range			
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.			Highest aggregated BW of the CA configuration			
Test S	CS as specifi	ed in Table 5.3.5-1.		Highest		
			Test Pa	rameters		
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
1	PCC	Default	Default	NI/A	DFT-s-OFDM QPSK	Outer_Full
	SCC	Deiault	Deidull	N/A	DFT-s-OFDM QPSK	Outer_Full
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

### Table 6.3A.4.2.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1, C.2 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3A.4.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity NR, Connected without release On according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3A.4.2.1.4.3.

6.3A.4.2.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2, and C.3 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.3A.4.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause9.2).
- 4. SS sends uplink scheduling information via PDCCH DCI format 0\_1 with TPC command 0dB for C\_RNTI to schedule the UL RMC according to Table 6.3.1.4.1-1 on PCC and SCC(s). Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Configure the UE transmitted output power to test point 1 in section 6.3A.4.2.1.4.3. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 8. Measure UE EIRP of the first subframe of each component carrier in the Tx beam peak direction in the measurement bandwidth specified in Table 6.3A.4.2.1.5-1 through Table 6.3A.4.2.1.5-3 for the specific channel bandwidth under test. EIRP test procedure is defined in Annex K. The measuring duration is one active uplink

subframe. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.

- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 10. Repeat test steps 1~9 for measurement for test point 2~3. The timing of the execution between each test point shall be larger than 20ms.
- NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

### 6.3A.4.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions:

### Table 6.3A.4.2.1.4.3-1: PUSCH-PowerControl (Test point 1) for power class 3

Derivation Path: TS 38.508-1 [10], Table 4.3.3-91						
Information Element	Value/remark	Comment	Condition			
PUSCH-PowerControl ::= SEQUENCE {						
tpc-Accumulation	disabled					
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0-	1 entry					
PUSCH-AlphaSets)) OF SEQUENCE {						
p0	-116		50MHz			
	-120		100MHz			
	-122		200MHz			
	-126		400MHz			
alpha	alpha1					
}						
}						

### Table 6.3A.4.2.1.4.3-2: PUSCH-PowerControl (Test point 2) for power class 3

Derivation Path: TS 38.508-1 [10], Table 4.3.3-91			
Information Element	Value/remark	Comment	Condition
PUSCH-PowerControl ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0-	1 entry		
PUSCH-AlphaSets)) OF SEQUENCE {			
p0	-112		50MHz
	-116		100MHz
	-118		200MHz
	-122		400MHz
alpha	alpha1		
}			
}			

### Table 6.3A.4.2.1.4.3-3: PUSCH-PowerControl (Test point 3) for power class 3

Derivation Path: TS 38.508-1 [10], Table 4.3.3-91						
Information Element	Value/remark	Comment	Condition			
PUSCH-PowerControl ::= SEQUENCE {						
tpc-Accumulation	disabled					
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0- PUSCH-AlphaSets)) OF SEQUENCE {	1 entry					
p0	-102		50MHz			
	-106		100MHz			
	-108		200MHz			
	-112		400MHz			
alpha	alpha1					
}						
}						

Derivation Path: 38.508-1[5], Table 4.6.3-168			
Information Element	Value/remark	Comment	Condition
ServingCellConfigCommon ::= SEQUENCE {			
ss-PBCH-BlockPower	1		SCS_60kHz
	4		SCS_120kHz
}			

### Table 6.3A.4.2.1.4.3-5: ServingCellConfigCommon

Condition		Explanation
SCS_60kHz		SCS=60kHz for SS/PBCH block
SCS_120kHz		SCS=120kHz for SS/PBCH block

### 6.3A.4.2.1.5 Test requirement

The measured EIRP in step 7 and 9 shall not to exceed the values specified in Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3.

### Table 6.3A.4.2.1.5-1: Test Requirements of Absolute power tolerance (Test point 1) for power class 3

	SCS	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measure	ed 60kHz	8.1	7.1	8.1	N/A	
power	120kHz	8.1	7.1	8.1	7.1	
Power tolerance		± (14+TT) dB				
defined	Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for e 4.	each frequency	and channel ba	andwidth is spe	cified in Table	6.3A.4.2.1.5-	

### Table 6.3A.4.2.1.5-2: Test Requirements of Absolute power tolerance (Test point 2) for power class 3

	SCS	Channel bandwidth / expected output power (dBm)			
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	12.1	11.1	12.1	N/A
power	120kHz	12.1	11.1	12.1	11.1
Power tolerance ± (12+TT) dB					
Note 1: The lower p	ower limit s	hall not exceed	d the minimum of	output power re	equirements
defined in s	defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the				
Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for each fre	equency and	d channel band	lwidth is specifie	ed in Table 6.3	A.4.2.1.5-5.

### Table 6.3A.4.2.1.5-3: Test Requirements of Absolute power tolerance (Test point 3) for power class 3

		SCS	Channel ba	Channel bandwidth / expected output power (dBm)				
			50 MHz	100 MHz	200 MHz	400 MHz		
Expected	Measured	60kHz	22.1	21.1	22.1	N/A		
рс	ower	120kHz	22.1	21.1	22.1	21.1		
P	ower toleran	ce	± (12+TT) dB					
Note 1:	ote 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.							
Note 2:								

### Table 6.3A.4.2.1.5-4: Test Tolerance (Test point 1) for power class 3

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

#### Table 6.3A.4.2.1.5-5: Test Tolerance (Test point 2 and Test point 3) for power class 3

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

### 6.3A.4.2.2 Absolute power tolerance for CA (3UL CA)

### 6.3A.4.2.2.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

6.3A.4.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA and 3DL CA.

6.3A.4.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.2.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1→ use Table 6.3A.4.2.2.4-1.
- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.2.5-1 and 6.3A.4.2.2.5-3.

	Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Low and High range				
5.5A.1 Config	Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Highest aggregated BW of the CA configuration				
Test S	CS as specifie	d in Table 5.3.5-1.		Highest			
			Test Para	ameters			
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)	
	PCC				DFT-s-OFDM QPSK	Outer_Full	
1	SCC1	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full	
	SCC2				DFT-s-OFDM QPSK	Outer_Full	
NOTE	1: The specifi 6.1-2 for P		each RB allocatior	n is defined in Tab	le 6.1-1 for PC2, PC	C3 and PC4 or Table	

### Table 6.3A.4.2.2.4-1: Test Configuration Table

### 6.3A.4.2.2.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3A.4.2.1.5-1  $\rightarrow$  use Table 6.3A.4.2.2.5-1.
- Instead of Table 6.3A.4.2.1.5-2  $\rightarrow$  use Table 6.3A.4.2.2.5-2.
- Instead of Table 6.3A.4.2.1.5-3  $\rightarrow$  use Table 6.3A.4.2.2.5-3.
- Instead of Table 6.3A.4.2.1.5-4  $\rightarrow$  use Table 6.3A.4.2.2.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.2.5-5.

### Table 6.3A.4.2.2.5-1: Test Requirements of Absolute power tolerance (Test point 1)

		SCS	Channel bandwidth / expected output power (dBm)				
			50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured 60kH			8.1	7.1	8.1	N/A	
power 120k			8.1	7.1	8.1	7.1	
Power tolerance $\pm$ (14+TT) dB							
Note 1: Th	ne lower p	power limit shall not exceed the minimum output power requirements					
de	defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the						
М	Max EIRP defined in sub-clause 6.2A.1.						
Note 2: T	for each	n frequency a	y and channel bandwidth is specified in Table 6.3A.4.2.2.5-				
4.				•			

	SCS	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured	60kHz	12.1	11.1	12.1	N/A	
power	120kHz	12.1	11.1	12.1	11.1	
Power tolerance ± (12+TT) dB						
Note 1: The lower power limit shall not exceed the minimum output power requirements						
defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the						
Max EIRP defined in sub-clause 6.2A.1.						
Note 2: TT for each frequency and channel bandwidth is specified in Table 6.3A.4.2.2.5-4.						

Table 6.3A.4.2.2.5-3: Test Requirements of Absolute power tolerance (	Test poin	it 3)
		/

	SCS	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured 60kHz 22.1 21.1 22.1 N					N/A	
power	120kHz	22.1	21.1	22.1	21.1	
Power tolerance ± (12+TT) dB						
defined in	The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for eac 4.	T for each frequency and channel bandwidth is specified in Table 6.3A.4.2.2.5-					

Table 6.3A.4.2.2.5-4: Test Tolerance (Test point 1)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

### Table 6.3A.4.2.2.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

### 6.3A.4.2.3 Absolute power tolerance for CA (4UL CA)

### 6.3A.4.2.3.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

6.3A.4.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA and 4DL CA.

#### 6.3A.4.2.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.3.4 Test description

6.3A.4.2.3.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1  $\rightarrow$  use Table 6.3A.4.2.3.4-1.

- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.3.5-1 and 6.3A.4.2.3.5-3.

Default Conditions									
Test E	nvironment a	s specified in TS	38.508-1 [10]	Normal					
subcla	use 4.1								
		s specified in TS		Low and High ra	ange				
		3] for different C							
			apped onto physical						
		ing to Table 6.1-							
			cified in subclause	Highest aggrega	ated BW of the CA	configuration			
		and 5.5A.2-2 for							
Configuration across bandwidth combination sets									
	rted by the U		F 4						
Test S	CS as specif	ied in Table 5.3.		Highest					
Teet	1		Test Par	DL RB UL RB allocation					
Test ID	СС	ChBw(MHz)	Test frequency	allocation	UL Modulation	(Note 1)			
	PCC				DFT-s-OFDM QPSK	Outer_Full			
1	SCC1	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full			
'	SCC2	Delault		Delauit	Derault	IN/A	DFT-s-OFDM QPSK	Outer_Full	
	SCC3				DFT-s-OFDM QPSK	Outer_Full			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.									

### Table 6.3A.4.2.3.4-1: Test Configuration Table

### 6.3A.4.2.3.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3S.4.2.1.5-1→ use Table 6.3A.4.2.3.5-1.
- Instead of Table 6.3S.4.2.1.5-2 $\rightarrow$  use Table 6.3A.4.2.3.5-2.
- Instead of Table 6.3S.4.2.1.5-3 → use Table 6.3A.4.2.3.5-3.
- Instead of Table 6.3A.4.2.1.5-4  $\rightarrow$  use Table 6.3A.4.2.3.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.3.5-5.

### Table 6.3A.4.2.3.5-1: Test Requirements of Absolute power tolerance (Test point 1)

		SCS	Channel bandwidth / expected output power (dBm)					
			50 MHz	100 MHz	200 MHz	400 MHz		
Expected N	/leasured	60kHz	8.1	7.1	8.1	N/A		
pow	/er	120kHz	8.1 7.1 8.1 7.1					
Power tolerance ± (14+TT) dB								
	defined in s	ower power limit shall not exceed the minimum output power requirements ed in sub-clause 6.3A.1, and the higher power limit shall not exceed the EIRP defined in sub-clause 6.2A.1.						
Note 2:				andwidth is spec	cified in Table	6.3A.4.2.3.5-		

	SCS	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured	60kHz	12.1	11.1	12.1	N/A	
power	power 120kHz 12.1 11.1 12.1 11.1				11.1	
Power tolerance ± (12+TT) dB						
defined in s	e lower power limit shall not exceed the minimum output power requirements fined in sub-clause 6.3A.1, and the higher power limit shall not exceed the ax EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for each 4.	n frequency a	and channel ba	andwidth is spec	cified in Table	6.3A.4.2.3.5-	

Table 6.3A.4.2.3.5-2: Test Requirements of Absolute power tolerance (Test point 2)
--

### Table 6.3A.4.2.3.5-3: Test Requirements of Absolute power tolerance (Test point 3)

	SCS	Channel ba	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz		
Expected Measured 60kHz 22.1 21.1 22.1 N/A					N/A		
power	power 120kHz 22.1 21.1 22.1 21.				21.1		
Power tolerance ± (12+TT) dB							
define	The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.						
Note 2: TT for 4.	or each frequency and channel bandwidth is specified in Table 6.3A.4.2.3.5-						

Table 6.3A.4.2.3.5-4: Test Tolerance	(Test	point 1)	,
	(	P • · · · /	

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

### Table 6.3A.4.2.3.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

### 6.3A.4.2.4 Absolute power tolerance for CA (5UL CA)

### 6.3A.4.2.4.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

### 6.3A.4.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA and 5DL CA.

#### 6.3A.4.2.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.4.4 Test description

6.3A.4.2.4.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1→ use Table 6.3A.4.2.4.4-1.
- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.4.5-1 and 6.3A.4.2.4.5-3.

			Default Co	onditions		
	nvironment a use 4.1	as specified in TS	38.508-1 [10]	Normal		
subcla classes	use [4.3.1.2. s, and PCC a	s specified in TS 3] for different C/ and SCCs are ma ing to Table 6.1-2	A bandwidth apped onto physical	Low and High ra	ange	
5.5A.1 Config	-1, 5.5A.2-1	and 5.5A.2-2 for ss bandwidth con		Highest aggrega	ated BW of the CA	configuration
Test S	CS as specif	ied in Table 5.3.5	5-1. Test Par	Highest		
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
	PCC				DFT-s-OFDM QPSK	Outer_Full
	SCC1				DFT-s-OFDM QPSK	Outer_Full
1	SCC2	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full
	SCC3				DFT-s-OFDM QPSK	Outer_Full
	SCC4				DFT-s-OFDM QPSK	Outer_Full
NOTE		cific configuration 1-2 for PC1.	of each RB allocatio	n is defined in Tal	ble 6.1-1 for PC2, P	C3 and PC4 or

# Table 6.3A.4.2.4.4-1: Test Configuration Table

#### 6.3A.4.2.4.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3A.4.2.1.5-1  $\rightarrow$  use Table 6.3A.4.2.4.5-1.
- Instead of Table 6.3A.4.2.1.5-2 $\rightarrow$  use Table 6.3A.4.2.4.5-2.
- Instead of Table 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.4.5-3.
- Instead of Table 6.3A.4.2.1.5-4 → use Table 6.3A.4.2.4.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.4.5-5.

## Table 6.3A.4.2.4.5-1: Test Requirements of Absolute power tolerance (Test point 1)

		SCS	Channel ba	ndwidth / expe	ected output p	oower (dBm)
			50 MHz	100 MHz	200 MHz	400 MHz
Expected	Measured	60kHz	8.1	7.1	8.1	N/A
pov	wer	120kHz	8.1	7.1	8.1	7.1
Po	ower toleran	се		± (14+	TT) dB	
	defined in s	ub-clause 6		d the minimum o higher power lin .1.		
Note 2:	TT for each 4.	frequency a	and channel ba	andwidth is spec	cified in Table	6.3A.4.2.4.5-

		SCS	Channel ba	ndwidth / expe	ected output p	oower (dBm)
			50 MHz	100 MHz	200 MHz	400 MHz
Expected	Measured	60kHz	12.1	11.1	12.1	N/A
ро	wer	120kHz	12.1	11.1	12.1	11.1
P	ower toleran	се		± (12+	TT) dB	
Note 1:	defined in s	ub-clause 6		d the minimum o higher power lin .1.		
Note 2:	TT for each 4.	frequency a	and channel ba	andwidth is spec	cified in Table	6.3A.4.2.4.5-

# Table 6.3A.4.2.4.5-3: Test Requirements of Absolute power tolerance (Test point 3)

	SCS	Channel ba	ndwidth / expe	ected output p	power (dBm)
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	22.1	21.1	22.1	N/A
power	120kHz	22.1	21.1	22.1	21.1
Power toler	ance		± (12+	TT) dB	
	n sub-clause 6		higher power li		
Note 2: TT for ea	ch frequency	and channel ba	andwidth is spe	cified in Table	6.3A.4.2.4.5-

Table 6.3A.4.2.4.5-4: Test Tolerance	(Test point 1)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# Table 6.3A.4.2.4.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# 6.3A.4.2.5 Absolute power tolerance for CA (6UL CA)

#### 6.3A.4.2.5.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

# 6.3A.4.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA and 6DL CA.

#### 6.3A.4.2.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.5.4 Test description

6.3A.4.2.5.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1→ use Table 6.3A.4.2.5.4-1.
- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.5.5-1 and 6.3A.4.2.5.5-3.

			Default Co	onditions		
		s specified in TS	38.508-1 [10]	Normal		
	use 4.1		20 500 4 [40]			
		s specified in TS ] for different C		Low and High ra	ange	
			apped onto physical			
		ng to Table 6.1-				
			cified in subclause	Highest aggrega	ated BW of the CA	configuration
		and 5.5A.2-2 for				
		s bandwidth con	nbination sets			
	rted by the UI	∟. ied in Table 5.3.	5-1	Highest		
10000			Test Par			
Test ID	сс	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
	PCC				DFT-s-OFDM QPSK	Outer_Full
	SCC1	]			DFT-s-OFDM QPSK	Outer_Full
1	SCC2	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full
1	SCC3	Delault	Delauit	IN/A	DFT-s-OFDM QPSK	Outer_Full
	SCC4				DFT-s-OFDM QPSK	Outer_Full
	SCC5				DFT-s-OFDM QPSK	Outer_Full
NOTE	1: The spec 6.1-2 for		of each RB allocation	n is defined in Tab	le 6.1-1 for PC2, PC	C3 and PC4 or Table

# Table 6.3A.4.2.5.4-1: Test Configuration Table

# 6.3A.4.2.5.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3A.4.2.1.5-1 → use Table 6.3A.4.2.5.5-1.
- Instead of Table 6.3A.4.2.1.5-2 $\rightarrow$  use Table 6.3A.4.2.5.5-2.
- Instead of Table 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.5.5-3.
- Instead of Table 6.3A.4.2.1.5-4  $\rightarrow$  use Table 6.3A.4.2.5.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.5.5-5.

## Table 6.3A.4.2.5.5-1: Test Requirements of Absolute power tolerance (Test point 1)

		SCS	Channel ba	ndwidth / expe	ected output p	oower (dBm)
			50 MHz	100 MHz	200 MHz	400 MHz
Expected	Measured	60kHz	8.1	7.1	8.1	N/A
рс	ower	120kHz	8.1	7.1	8.1	7.1
P	ower toleran	ce		± (14+	TT) dB	
Note 1:	defined in s Max EIRP of	sub-clause 6 defined in su	.3A.1, and the lb-clause 6.2A		mit shall not e	ceed the
Note 2:	TT for each 4.	frequency a	and channel ba	andwidth is spec	cified in Table	6.3A.4.2.5.5-

	SCS	Channel ba	ndwidth / expe	ected output p	oower (dBm)
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	12.1	11.1	12.1	N/A
power	120kHz	12.1	11.1	12.1	11.1
Power toleran	се		± (12+	TT) dB	
Note 1: The lower p	ower limit s	hall not exceed	d the minimum o	output power re	equirements
defined in s	ub-clause 6	.3A.1, and the	higher power lii	mit shall not ex	ceed the
Max EIRP of	defined in su	b-clause 6.2A	.1.		
Note 2: TT for each fre	equency and	d channel band	lwidth is specifie	ed in Table 6.3	A.4.2.5.5-4.

Table 6.3A.4.2.5.5-2: Test Requirements of Absolute power tolerance (Test point 2)
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Table 6.3A.4.2.5.5-3: Test Requirements of Absolute power tolerand	ce (Test point 3)

		SCS	Channel bandwidth / expected output power (dBm)			
			50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured		60kHz	22.1	21.1	22.1	N/A
рс	power 120kHz 22.1 21.1 22.1 21.1					
F	Power tolerance		± (12+TT) dB			
Note 1:	Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2:	TT for each frequency and channel bandwidth is specified in Table 6.3A.4.2.5.5- 4.					

# Table 6.3A.4.2.5.5-4: Test Tolerance (Test point 1 and Test point 2)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# Table 6.3A.4.2.5.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# 6.3A.4.2.6 Absolute power tolerance for CA (7UL CA)

# 6.3A.4.2.6.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

6.3A.4.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA and 7DL CA.

6.3A.4.2.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.6.4 Test description

6.3A.4.2.6.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1→ use Table 6.3A.4.2.6.4-1.
- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.6.5-1 and 6.3A.4.2.6.5-3.

ies as specified .1.2.3] for differe CC and SCCs a cording to Table ination setting as .2-1 and 5.5A.2-	s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Normal Low and High r Highest aggreg Highest rameters DL RB allocation	ange ated BW of the CA o	configuration
.1.2.3] for difference CC and SCCs a coording to Table ination setting as .2-1 and 5.5A.2- across bandwidth he UE. pecified in Table ChBw(Mit	ent CA bandwidth re mapped onto physical 6.1-2. s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Highest aggreg Highest rameters DL RB	ated BW of the CA	
.1.2.3] for difference CC and SCCs a coording to Table ination setting as .2-1 and 5.5A.2- across bandwidth he UE. pecified in Table ChBw(Mit	ent CA bandwidth re mapped onto physical 6.1-2. s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Highest aggreg Highest rameters DL RB	ated BW of the CA	
CC and SCCs a cording to Table ination setting as .2-1 and 5.5A.2- across bandwidth he UE. pecified in Table ChBw(MI	re mapped onto physical 6.1-2. s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Highest rameters DL RB		
cording to Table ination setting as .2-1 and 5.5A.2- across bandwidth he UE. pecified in Table	e 6.1-2. s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Highest rameters DL RB		
ination setting as .2-1 and 5.5A.2- across bandwidth he UE. pecified in Table	s specified in subclause 2 for the CA h combination sets 5.3.5-1. Test Pa	Highest rameters DL RB		
across bandwidt he UE. pecified in Table ChBw(MI	h combination sets 5.3.5-1. Test Pa	rameters DL RB	III Modulation	UL RB allocation
he UE. pecified in Table	5.3.5-1. Test Pa	rameters DL RB	III Modulation	UL RB allocation
ChBw(Mi	Test Pa	rameters DL RB	UI Modulation	UL RB allocatior
ChBw(M	Test Pa	rameters DL RB	UI Modulation	UL RB allocation
	Hz) Test frequency		UI Modulation	UL RB allocation
		anocation		(Note 1)
			DFT-s-OFDM QPSK	Outer_Full
:1			DFT-s-OFDM QPSK	Outer_Full
2			DFT-s-OFDM QPSK	Outer_Full
C3 Defaul	t Default	N/A	DFT-s-OFDM QPSK	Outer_Full
24			DFT-s-OFDM QPSK	Outer_Full
5			DFT-s-OFDM QPSK	Outer_Full
6			DFT-s-OFDM QPSK	Outer_Full
	4 5 6	4 5 6 specific configuration of each RB allocatio	4 5 6 specific configuration of each RB allocation is defined in Tab	3     Default     N/A     QPSK       4     0     0     0       5     0     0     0       6     0     0     0

# Table 6.3A.4.2.6.4-1: Test Configuration Table

#### 6.3A.4.2.6.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3A.4.2.1.5-1→ use Table 6.3A.4.2.6.5-1.
- Instead of Table 6.3A.4.2.1.5-2→ use Table 6.3A.4.2.6.5-2.
- Instead of Table 6.3A.4.2.1.5-3→ use Table 6.3A.4.2.6.5-3.
- Instead of Table 6.3A.4.2.1.5-4 $\rightarrow$  use Table 6.3A.4.2.6.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.6.5-5.

# Table 6.3A.4.2.6.5-1: Test Requirements of Absolute power tolerance (Test point 1)

		SCS	Channel bandwidth / expected output power (dBm)					
			50 MHz	100 MHz	200 MHz	400 MHz		
Expected	d Measured 60kHz 7.1 8.1 7.1 N/A				N/A			
pc	ower	120kHz	7.1 8.1 7.1 8.1					
P	Power tolerance		± (14+TT) dB					
Note 1:	ote 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.							
Note 2:	TT for each 4.	frequency a	and channel ba	andwidth is spec	cified in Table	6.3A.4.2.6.5-		

		SCS	Channel bandwidth / expected output power (dBm)				
			50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured 60kHz 12.1 11.1 12.1				N/A			
рс	ower	120kHz 12.1 11.1 12.1 11.1					
P	Power tolerance		± (12+TT) dB				
Note 1:	Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.						
Note 2:	TT for each frequency and channel bandwidth is specified in Table 6.3A.4.2.6.5- 4.						

# Table 6.3A.4.2.6.5-3: Test Requirements of Absolute power tolerance (Test point 3)

	SCS	Channel bandwidth / expected output power (dBm)				
		50 MHz	100 MHz	200 MHz	400 MHz	
Expected Measured	60kHz 22.1 21.1 22.1 N/A					
power	120kHz	Hz 22.1 21.1 22.1 21.1				
Power tolerance		± (12+TT) dB				
defined in s	te 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for each 4.	each frequency and channel bandwidth is specified in Table 6.3A.4.2.6.5-					

Table 6.3A.4.2.6.5-4: Test Tolerance	Test	point 1)	)
		P • · · · /	

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# Table 6.3A.4.2.6.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# 6.3A.4.2.7 Absolute power tolerance for CA (8UL CA)

# 6.3A.4.2.7.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

To verify the ability of the UE transmitter to set its initial output power to a specific value at the start of a contiguous transmission or non-contiguous transmission with a long transmission gap, i.e. transmission gap is larger than 20 ms.

#### 6.3A.4.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

# 6.3A.4.2.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.3A.4.2.0.

6.3A.4.2.7.4 Test description

6.3A.4.2.7.4.1 Initial condition

Same as in clause 6.3A.4.2.1.4.1 with the following exceptions:

- Instead of Table 6.3A.4.2.1.4.1-1→ use Table 6.3A.4.2.7.4-1.
- Instead of Table 6.3A.4.2.1.5-1 through 6.3A.4.2.1.5-3 → use Table 6.3A.4.2.7.5-1 and 6.3A.4.2.7.5-3.

Toot E	nvironmont o	s specified in TS	Default C	Normal		
	use 4.1		5 30.500-1 [10]	Normai		
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Low and High range			
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.			Highest aggreg	ated BW of the CA	configuration	
Test S	CS as specif	ied in Table 5.3.		Highest		
<b>T</b>	[		Test Par		T	
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
	PCC				DFT-s-OFDM QPSK	Outer_Full
	SCC1				DFT-s-OFDM QPSK	Outer_Full
					DFT-s-OFDM	
	SCC2				QPSK	Outer_Full
4	SCC2 SCC3	Default	Default	N1/A		Outer_Full Outer_Full
1		Default	Default	N/A	QPSK DFT-s-OFDM	
1	SCC3	- Default	Default	N/A	QPSK DFT-s-OFDM QPSK DFT-s-OFDM	Outer_Full
1	SCC3 SCC4	Default	Default	N/A	QPSK DFT-s-OFDM QPSK DFT-s-OFDM QPSK DFT-s-OFDM	Outer_Full Outer_Full

# Table 6.3A.4.2.7.4-1: Test Configuration Table

# 6.3A.4.2.7.5 Test requirement

Same as in clause 6.3A.4.2.1.5 with the following exceptions:

- Instead of Table 6.3A.4.2.1.5-1→ use Table 6.3A.4.2.7.5-1.
- Instead of Table 6.3A.4.2.1.5-2 $\rightarrow$  use Table 6.3A.4.2.7.5-2.
- Instead of Table 6.3A.4.2.1.5-3→ use Table 6.3A.4.2.7.5-3.
- Instead of Table 6.3A.4.2.1.5-4 → use Table 6.3A.4.2.7.5-4.
- Instead of Table 6.3A.4.2.1.5-5  $\rightarrow$  use Table 6.3A.4.2.7.5-5.

	SCS	Channel bandwidth / expected output power (dBm)			oower (dBm)
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	8.1	7.1	8.1	N/A
power	120kHz	8.1	7.1	8.1	7.1
Power tolerance ± (14+TT) dB					
Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for each 4.					

 Table 6.3A.4.2.7.5-1: Test Requirements of Absolute power tolerance (Test point 1)

# Table 6.3A.4.2.7.5-2: Test Requirements of Absolute power tolerance (Test point 2)

	SCS	Channel bandwidth / expected output power (dBm)			oower (dBm)
		50 MHz	100 MHz	200 MHz	400 MHz
Expected Measured	60kHz	12.1	11.1	12.1	N/A
power	120kHz	12.1	11.1	12.1	11.1
Power tolerance ± (12+TT) dB					
Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2: TT for each 4.					

# Table 6.3A.4.2.7.5-3: Test Requirements of Absolute power tolerance (Test point 3)

		SCS	Channel bandwidth / expected output power (dBm)			
			50 MHz	100 MHz	200 MHz	400 MHz
Expected	Measured	60kHz	22.1	21.1	22.1	N/A
power 12		120kHz	22.1	21.1	22.1	21.1
F	Power tolerance ± (12+TT) dB					
Note 1:	Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3A.1, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2A.1.					
Note 2:	ote 2: TT for each frequency and channel bandwidth is specified in Table 6.3A.4.2.7.5- 4.				6.3A.4.2.7.5-	

Table 6.3A.4.2.7.5-4: Test Tolerance (Test point 1)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# Table 6.3A.4.2.7.5-5: Test Tolerance (Test point 2 and Test point 3)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[FFS] dB	[FFS] dB

# 6.3D Output power dynamics for UL MIMO

# 6.3D.1 Minimum output power for UL MIMO

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

Measurement Uncertainty and Test Tolerances are FFS.

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# 6.3D.1.1 Test purpose

To verify the UE's ability to transmit with a broadband output power below the value specified in the test requirement when the power is set to a minimum value.

# 6.3D.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

# 6.3D.1.3 Minimum conformance requirements

The minimum output power is defined as the mean power in at least one subframe (1ms).

# 6.3D.1.3.1 Minimum output power for UL MIMO for power class 1

For UE supporting UL MIMO, the minimum controlled output power is defined as the EIRP, i.e. the sum of the power in the channel bandwidth for all transmit bandwidth configurations (resource blocks), when the UE power is set to a minimum value. The minimum output power shall not exceed the values specified in Table 6.3.1.3.1-1. The minimum power is verified in beam locked mode with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

# 6.3D.1.3.2 Minimum output power for UL MIMO for power class 2, 3 and 4

For UE supporting UL MIMO, the minimum controlled output power is defined as the EIRP, i.e. the sum of the power in the channel bandwidth for all transmit bandwidth configurations (resource blocks), when the UE power is set to a minimum value. The minimum output power shall not exceed the values specified in Table 6.3.1.3.2-1. The minimum power is verified in beam locked mode with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3D.1.

- 6.3D.1.4 Test description
- 6.3D.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in Table 6.3D.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.3D.1.4.1-1: Test Configuration Table

	Initia	I Conditions			
Test Envir subclause	onment as specified in TS 38.508-1 [10] 4.1	Normal			
Test Frequesubclause	uencies as specified in TS 38.508-1 [10] 4.3.1	Low range, Mid range, High range			
Test Channel Bandwidths as specified in TS 38.508- 1 [10] subclause 4.3.1		Lowest, Mid, Highest			
Test SCS	as specified in Table 5.3.5-1.	Highest			
	Test	Parameters			
	Downlink Configuration	Uplink Configuration			
Test ID	N/A for minimum output power test case	Modulation	RB allocation (NOTE 1)		
1		CP-OFDM QPSK	Outer_Full		
	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.				

1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.

- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.3D.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3D.1.4.3.

#### 6.3D.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.1.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [5] subclause 4.3.6.1.1.2.
- 3. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 2. Send continuously uplink power control "down" commands in every uplink scheduling information to the UE; allow at least 200ms starting from the first TPC command in this step to ensure that the UE transmits at its minimum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure UE EIRP in the Tx beam peak direction in the measurement bandwidth specified in Table 6.3D.1.5-1 and Table 6.3D.1.5-2 for the specific channel bandwidth under test. EIRP test procedure is defined in Annex K. The measuring duration is at least one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.3D.1.4.3 Message contents

Message contents are according to TS 38.508-1 [5] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

### 6.3D.1.5 Test requirement

The minimum EIRP, derived in step 5 shall not exceed the values specified in Table 6.3D.1.5-1 and Table 6.3D.1.5-2.

#### Table 6.3D.1.5-1: Minimum output power for power class 1

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	4+TT	47.58
	100	4+TT	95.16
	200	4+TT	190.20
	400	4+TT	380.28

Operating band	Channel bandwidth (MHz)	Minimum output power (dBm)	Measurement bandwidth (MHz)
n257, n258, n260, n261	50	-13+TT	47.58
	100	-13+TT	95.16
	200	-13+TT	190.20
	400	-13+TT	380.28

Table 6.3D.1.5-2: Minimum output power for power class 2, 3, and 4

# 6.3D.2 Transmit OFF power for UL MIMO

# 6.3D.3 Transmit ON/OFF time mask for UL MIMO

# 6.3D.3.1 General ON/OFF time mask for UL MIMO

Editor's Note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerances are FFS.
- Test requirement of ON power is FFS.
- Testability of OFF power needs further study.
- OTA test procedure for UL-MIMO is still under investigation

#### 6.3D.3.1.1 Test purpose

To verify that the general ON/OFF time mask meets the requirements given in 6.3D.3.1.5. Transmission of the wrong power increases interference to other channels, or increases transmission errors in the uplink channel.

#### 6.3D.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

#### 6.3D.3.1.3 Minimum conformance requirements

For UE supporting UL MIMO, the ON/OFF time mask requirements in subclause 6.3.3 apply. The requirements shall be met with the UL MIMO configurations specified in Table 6.2D.1.3.3-3.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.3D.3.

- 6.3D.3.1.4 Test description
- 6.3D.3.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, and are shown in table 6.3D.3.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initia	I Conditions		
Test Environment as specified in TS 38.508-1 [10] subclause 4.1		Normal		
	encies as specified in TS 38.508-1 [10]	Low range, Mid range, High range		
Test Channel Bandwidths as specified in TS 38.508- 1 [10] subclause 4.3.1		Lowest, Mid, Highest		
Test SCS	as specified in Table 5.3.5-1.	Highest		
	Test	Parameters		
	Downlink Configuration	Uplink Configuration		
Test ID	N/A for maximum output power test case	Modulation	RB allocation (NOTE 1)	
1		DFT-s-OFDM QPSK	Outer_Full	
	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.			

# Table 6.3D.3.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channels are set according to Table 6.3D.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3D.3.1.4.3.

#### 6.3D.3.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.3.3.2.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [5] subclause 4.3.6.1.1.2.
- 2. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 4) for the UE Tx beam selection to complete.
- 3. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 4. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.1.5-1. EIRP test procedure is defined in Annex K. The period of the measurement shall be the slot prior to the PUSCH transmission, excluding a transient period of 5 µs in the end of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.
- 5. For UE transmission ON power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.1.5-2. EIRP test procedure is defined in Annex K. The period of the measurement shall be one slot with PUSCH transmission. EIRP is calculated considering both polarizations, theta and phi. For TDD slots with transient periods are not under test.
- 6. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.1.5-1. EIRP test procedure is defined in Annex K. The period of the measurement shall be the slot following the PUSCH transmission, excluding a transient period of 5 μs at the beginning of the slot and any DL periods. EIRP is calculated considering both polarizations, theta and phi.

7. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

## 6.3D.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [5] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

# Table 6.3D.3.1.4.3-1: PUSCH-ConfigCommon

Derivation Path: TS 38.508-1[10], Table 4.6.3-119			
Information Element	Value/remark	Comment	Condition
PUSCH-ConfigCommon ::= SEQUENCE {			
tpc-Accumulation	disabled		
p0-AlphaSets SEQUENCE (SIZE (1maxNrofP0-	1 entry		
PUSCH-AlphaSets)) OF SEQUENCE {			
p0-NominalWithGrant	-102		50MHz
	-106		100MHz
	-108		200MHz
	-112		400MHz
alpha	alpha1		
}			
}			

# Table 6.3D.3.1.4.3-2: ServingCellConfigCommon

Derivation Path: 38.508-1[5], Table 4.6.3-168			
Information Element	Value/remark	Comment	Condition
ServingCellConfigCommon ::= SEQUENCE {			
ss-PBCH-BlockPower	1		SCS_60kHz
	4		SCS_120kH
			Z
}			

Condition	Explanation
SCS_60kHz	SCS=60kHz for SS/PBCH block
SCS_120kHz	SCS=120kHz for SS/PBCH block

# 6.3D.3.1.5 Test requirement

The requirement for the EIRP measured in steps 4, 5 and 6 of the test procedure shall not exceed the values specified in Table 6.3D.3.1.5-1 and 6.3D.3.1.5-2.

# Table 6.3D.3.1.5-1: Test requirement of OFF power of General ON/OFF time mask for UL MIMO

	Channel bandwi	Channel bandwidth / minimum output power / measurement bandwidth						
	50 MHz	100 MHz	200 MHz	400 MHz				
Transmit OFF power		≤ -30+TT dBm						
Transmission OFF Measurement bandwidth	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz				
Note 1:       Core requirements cannot be tested due to testability issue and test requirement includes relaxation to achieve impact from test system noise to measurement results = 1.0 dB (Minimum requirement + relaxation R).         Note 2:       Relaxation R is specified in Table 6.3D.3.1.5-3.								

	SCS	SCS Channel bandwidth / measureme bandwidth			ement
	[kHz]	50 MHz	100 MHz	200 MHz	400 MHz
Expected Transmission ON	60	22.1	21.1	22.1	N/A
power for DFT-s- OFDM	120	22.1	21.1	22.1	21.1
Power tolerar	nce		± (14-	-TT)dB	
Note 1: The low	ne lower power limit shall not exceed the minimum output power				
requirements defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2.1.3.					

#### Table 6.3D.3.1.5-2: Test requirement of ON power of General ON/OFF time mask for UL MIMO

Table 6.3D.3.1.5-3: Relaxation required for OFF power for PC3 UEs

Operating band	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n261	[19.4] dB	[22.4] dB	[25.4] dB	[28.4] dB
n260	[21.5] dB	[24.5] dB	[27.5] dB	[30.5] dB

#### Table 6.3D.3.1.5-4: Test Tolerance for ON power

FFS

# 6.3D.3.2 to 6.3D.3.3

# 6.3D.3.4 SRS time mask for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL-MIMO is still under investigation
- Measurement Uncertainty and Test Tolerances are FFS.
- Testability of OFF power needs further study.

# 6.3D.3.4.1 Test purpose

To verify that the SRS time mask for UL MIMO meets the requirements given in 6.3D.3.4.5.

The transmit ON/OFF time mask defines the transient period(s) allowed

- between transmit OFF power and transmit ON power symbols (transmit ON/OFF)

Unless otherwise stated the minimum requirements in clause 6 apply also in transient periods.

Transmission of the wrong power increases interference to other channels, or increases transmission errors in the uplink channel.

# 6.3D.3.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that support UL MIMO.

# 6.3D.3.4.3 Minimum conformance requirements

The transmit ON/OFF time mask is defined as a directional requirement. The requirement is verified in beam locked mode at beam peak direction. The maximum allowed EIRP OFF power level is -30dBm at beam peak direction. The requirement is verified with the test metric of EIRP (Link=TX beam peak direction, Meas=Link angle).

In the case of a single SRS transmission, the ON power is defined as the mean power over the symbol duration excluding any transient period; Figure 6.3D.3.4.3-1.

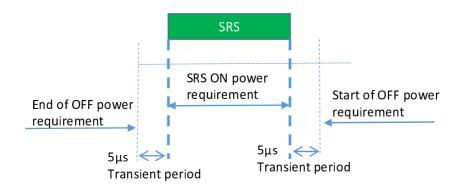


Figure 6.3D.3.4.3-1: Single SRS time mask for NR UL transmission

In the case of multiple consecutive SRS transmission, the ON power is defined as the mean power for each symbol duration excluding any transient period. See Figure 6.3D.3.4.3-2.

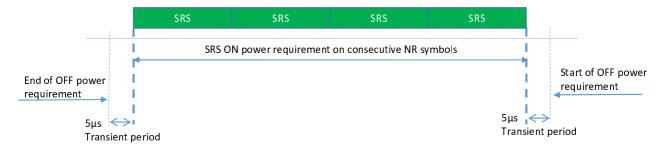


Figure 6.3D.3.4.3-2: Consecutive SRS time mask for the case when no power change is required

When power change between consecutive SRS transmissions is required, then Figure 6.3D.3.4.3-3 and 6.3D.3.4.3-4 apply.

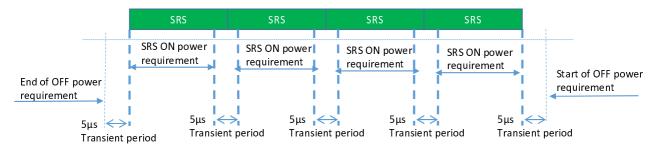
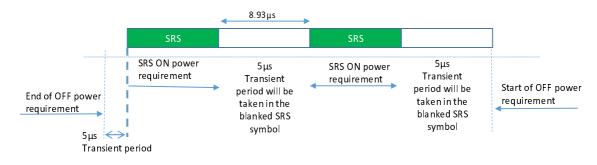


Figure 6.3D.3.4.3-3: Consecutive SRS time mask for the case when power change is required and when 60kHz SCS is used in FR2



# Figure 6.3D.3.4.3-4: Consecutive SRS time mask for the case when power change is required and when 120kHz SCS is used in FR2

The requirements shall be met with the UL MIMO configuration specified in Table 6.3D.3.4.3-1.

Table 6.3D.3.4.3-1: UL MIMO configuration

Transmission scheme	DCI format	Codebook Index
Codebook based uplink	DCI format 0_1	Codebook index 0

6.3D.3.4.4 Test description

6.3D.3.4.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in Table 6.3D.3.4.4.1-1. The details of the uplink and downlink reference measurement channels (RMCS) are specified in Annexes A.2 and A.3

	Initial Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]				Normal,			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1]			Low range, Mid R	ange, High range			
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause [4.3.1]			Lowest, Mid, Highest				
Test S0	CS as spec	ified in Tab	ole 5.3.5-1		Lowest, Highest		
			Test Pa	aram			
Test ID	ChBw	SCS	Downlink Configuration	• · · · · · · · · · · · · · · · · · · ·			
			N/A for	Modulation		<b>RB allocation (NOTE 1)</b>	
1	50	60kHz 120kHz	maximum output power test case	DF	T-s-OFDM QPSK	Outer_Full	
2	100	60kHz 120kHz					
3	200	60kHz 120kHz					
4	400	120kHz					
NOTE	NOTE 1: The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

# Table 6.3D.3.4.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C3.0, and uplink signals according to Annex G.0, G.1 and G3.0.
- 4. The UL Reference Measurement Channels are set according to Table 6.3D.3.4.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.3D.3.4.4.3.

# 6.3D.3.4.4.2 Test procedure

- 1. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 4) for the UE Tx beam selection to complete.
- 2. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 3. The SS measure the UE transmission OFF power during the 10 OFDM symbols for 60kHz SCS and 10 OFDM symbols for 120kHz SCS, preceding the SRS symbol excluding a transient period of 5  $\mu$ s.
- 4. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.4.4.1-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be during the 10 OFDM symbols for 60kHz SCS and 10 OFDM symbols for 120kHz SCS, preceding the SRS symbol excluding a transient period of 5 μs. EIRP is calculated considering polarizations, theta and phi.
- 5. For UE transmission ON power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.4.4.1-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the SRS transmission during 4 OFDM symbols for 60kHz SCS and 4 OFDM symbols for 120kHz SCS. EIRP is calculated considering polarizations, theta and phi.

6. For UE transmission OFF power, measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration, which shall meet the requirements described in Table 6.3D.3.4.4.1-1. EIRP test procedure is defined in Annex K.1.3. The period of the measurement shall be the slot following the SRS under test, excluding a transient period of 5 μs. EIRP is calculated considering polarizations, theta and phi.

### 6.3D.3.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions.

# Table 6.3D.3.4.4.3-1: BWP-UplinkDedicated

Derivation Path: TS 38.508-1 [10], Table 4.6.3-15 srs-Config with condition DCI\_0\_1

# Table 6.3D.3.4.4.3-2: SRS-Config: SRS time mask for UL MIMO measurement

Information Element	Value/remark		
	value/remark	Comment	Condition
SRS-Config ::= SEQUENCE {			
srs-ResourceSetToAddModList SEQUENCE	[1 entry]		
(SIZE(0maxNrofSRS-ResourceSets)) OF			
SEQUENCE {			
alpha	alpha1		
p0	-116		FR2_50MHz
	-120		FR2_100 MHz
	-122		FR2_200 MHz
	-126		FR2_400 MHz
}			
srs-ResourceToAddModList SEQUENCE	1 entry		
(SIZE(1maxNrofSRS-Resources)) OF SEQUENCE {			
resourceMapping SEQUENCE {			
nrofSymbols	n4		SCS 60 kHz
			SCS 120 kHz
}			
freqHopping SEQUENCE {			
c-SRS	17 (BW 50 MHz)		SCS 60 kHz
	30 (BW 100 MHz)		
	59 (BW 200 MHz)		
	9 (BW 50 MHz)		SCS 120 kHz
	17 (BW 100 MHz)		
	30 (BW 200 MHz)		
	59 (BW 400 MHz)		
}			
resourceType CHOICE {			
periodic SEQUENCE {			
periodicityAndOffset-p CHOICE {			
s120	16		SCS 60 kHz
s140	32		SCS 120 kHz
}			
}			
}			
tpc-Accumulation	disabled		
}			

Derivation Path: 38.508-1[5], Table 4.6.3-168			
Information Element	Value/remark	Comment	Condition
ServingCellConfigCommon ::= SEQUENCE {			
ss-PBCH-BlockPower	1		SCS_60kHz
	4		SCS_120kHz
}			

# Table 6.3D.3.4.4.3-3: ServingCellConfigCommon

Condition	Explanation
SCS_60kHz	SCS=60kHz for SS/PBCH block
SCS_120kHz	SCS=120kHz for SS/PBCH block

# 6.3D.3.4.5 Test requirement

The ON/OFF power of SRS time mask for UL MIMO shall not exceed the values specified in Table 6.3D.3.4.5-1 to Table 6.3D.3.4.5-4.

# Table 6.3D.3.4.5-1: Test requirement of OFF power of SRS time mask for UL MIMO ON/OFF time mask

	Channel bandy	Channel bandwidth/Opera Output Power [dBm] / measurement bandwidth					
	50	100	200	400			
	MHz	MHz	MHz	MHz			
Transmit OFF		≤ -30+TT	F+R dBm				
power							
Transmission OFF	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz			
measurement							
bandwidth							
Note 1: Core requirements cannot be tested due to testability issue and test requirement includes relaxation to achieve impact from test system noise to measurement results = 1.0 dB (Minimum requirement + relaxation R).							
Note 2: Relaxatio	Relaxation R is specified in Table 6.3D.3.4.5-3.						

# Table 6.3D.3.4.5-2: Test requirement of ON power of SRS for UL MIMO ON/OFF time mask

	SCS	Chann	Channel bandwidth / measurement bandwidth				
	[kHz]	50 MHz	100 MHz	200 MHz	400 MHz		
Expected Transmission ON	60	8.1 dBm	7.1 dBm	8.1 dBm	N/A		
power for DFT-s- OFDM	120	8.1 dBm	7.1 dBm	8.1 dBm	7.1 dBm		
ON		± (14+TT) dB					
Power toleran	се						
Note 1: The lower power limit shall not exceed the minimum output power requirements defined in sub-clause 6.3.2.3, and the higher power limit shall not exceed the Max EIRP defined in sub-clause 6.2.1.3.							
Note 2: TT for ea							

Operating band	50 MHz	100 MHz	200 MHz	400 MHz
n257, n258, n261	[19.4] dB	[22.4] dB	[25.4] dB	[28.4] dB
n260	[21.5] dB	[24.5] dB	[27.5] dB	[30.5] dB

#### Table 6.3D.3.4.5-4: Test Tolerance for SRS time mask for UL-MIMO ON power

Test Metric	FR2a	FR2b
DUT ≤ 30 cm	[TBD] dB	[TBD] dB

# 6.4 Transmit signal quality

# 6.4.1 Frequency error

Editor's note: The following aspects of the clause are for future consideration:

Testing of extreme conditions for FR2 is FFS.

#### 6.4.1.1 Test purpose

This test verifies the ability of both, the receiver and the transmitter, to process frequency correctly.

Receiver: to extract the correct frequency from the stimulus signal, offered by the System simulator, under ideal propagation conditions and low level.

Transmitter: to derive the correct modulated carrier frequency from the results, gained by the receiver.

#### 6.4.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.4.1.3 Minimum conformance requirements

The UE basic measurement interval of modulated carrier frequency is 1 UL slot. The mean value of basic measurements of UE modulated carrier frequency shall be accurate to within  $\pm 0.1$  PPM observed over a period of 1 msec of cumulated measurement intervals compared to the carrier frequency received from the NR gNB.

The frequency error is defined as a directional requirement. The requirement is verified in beam locked mode with the test metric of Frequency (Link=TX beam peak direction, Meas=Link angle).

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4.1

6.4.1.4 Test description

#### 6.4.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 6.4.1.4.1-1. The details of the uplink and downlink reference measurement channels (RMCs) are specified in Annexes A.2 and A.3. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initial Conditions					
Test Environment as specified in TS 38.508-1 [10]		Normal, [TL/NC, TH/NC]				
subclause						
Test Frequ	encies as specified	in TS 38.508-1 [10]	Mid range			
subclause	4.3.1					
Test Chan	nel Bandwidths as s	pecified in TS 38.508-	Highest			
1 [10] subo	lause 4.3.1		5			
Test SCS a	as specified in Table	5.3.5-1.	Lowest			
		Test	Parameters			
	Downlink	Configuration	Uplink Configuration			
Test ID	Modulation	RB allocation	Modulation RB allocation			
1	CP-OFDM	Full RB (NOTE 1)	DFT-s-OFDM QPSK	REFSENS (NOTE 2)		
NOTE 1:	NOTE 1: Full RB allocation shall be used per each SCS and channel BW as specified in Table 7.3.2.4.1-2.					
NOTE 2:	NOTE 2: REFSENS refers to Table 7.3.2.4.1-3 which defines uplink RB configuration and start RB location for					
each SCS, channel BW and NR band.						

# Table 6.4.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The DL and UL Reference Measurement channels are set according to Table 6.4.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4.1.4.3

# 6.4.1.4.2 Test procedure

- 1. Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2. SS transmits PDSCH via PDCCH DCI format 1\_0 for C\_RNTI to transmit the DL RMC according to Table 6.4.1.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 3. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction and apply the associated polarization for the DL, both found with a 3D EIRP scan as performed in Annex K.1.1. Connect the SS (System Simulator) with the DUT through the measurement antenna with polarization reference PolLink to form the TX beam towards the TX beam peak direction and respective polarization. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. Send continuously uplink power control "up" commands to the UE in every uplink scheduling information to the UE so that the UE transmits at P<sub>UMAX</sub> level for the duration of the test. Allow at least 200ms starting from the first TPC Command for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 7. Measure the Frequency Error using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization of the UL. For TDD, only slots consisting of only UL symbols are under test.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.4.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with DFT-s-OFDM condition in Table 4.6.3-118 PUSCH-Config and with the exceptions in subclause 7.3.2.4.3 and Table 7.3.2.5-3.

#### 6.4.1.5 Test requirement

The 10 frequency error  $\Delta f$  results for the  $\theta$ -polarization or the *n* frequency error  $\Delta f$  results for the  $\varphi$ -polarization must fulfil the test requirement:

$$|\Delta f| \le (0.1 \text{ PPM} + 0.005 \text{ PPM}),$$

# 6.4.2 Transmit modulation quality

Transmit modulation quality defines the modulation quality for expected in-channel RF transmissions from the UE. The transmit modulation quality is specified in terms of:

- Error Vector Magnitude (EVM) for the allocated resource blocks (RBs)
- EVM equalizer spectrum flatness derived from the equalizer coefficients generated by the EVM measurement process
- Carrier leakage
- In-band emissions for the non-allocated RB

All the parameters defined in subclause 6.4.2 are defined using the measurement methodology specified in Annex E.

All the requirements in 6.4.2 are defined as directional requirement. The requirements are verified in beam locked mode on beam peak direction, with parameter *maxRank* (as defined in TS 38.331 [19]) set to 1. The requirements are applicable to UL transmission from each configurable antenna port (as defined in TS 38.331 [19]) of UE, enabled one at a time.

In case the parameter 3300 or 3301 is reported from UE via *txDirectCurrentLocation* IE (as defined in TS 38.331 [19]), carrier leakage measurement requirement in subclause 6.4.2.2 and 6.4.2.3 shall be waived, and the RF correction with regard to the carrier leakage and IQ image shall be omitted during the calculation of transmit modulation quality.

# 6.4.2.1 Error vector magnitude

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.

# 6.4.2.1.1 Test Purpose

The Error Vector Magnitude is a measure of the difference between the reference waveform and the measured waveform. This difference is called the error vector. Before calculating the EVM, the measured waveform is corrected by the sample timing offset and RF frequency offset. Then the carrier leakage shall be removed from the measured waveform before calculating the EVM.

The measured waveform is further equalised using the channel estimates subjected to the EVM equaliser spectrum flatness requirement specified in sub-clauses 6.4.2.4.3 and 6.4.2.5.3. For DFT-s-OFDM waveforms, the EVM result is defined after the front-end FFT and IDFT as the square root of the ratio of the mean error vector power to the mean reference power expressed as a %. For CP-OFDM waveforms, the EVM result is defined after the front-end FFT as the square root of the mean reference power expressed as a %.

The basic EVM measurement interval in the time domain is one preamble sequence for the PRACH and the duration of PUCCH/PUSCH channel, or one hop, if frequency hopping is enabled for PUCCH and PUSCH in the time domain. The EVM measurement interval is reduced by any symbols that contain an allowable power transient as defined in subclause 6.3.3.3.

# 6.4.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

# 6.4.2.1.3 Minimum conformance requirements

The RMS average of the basic EVM measurements for the average EVM case, and for the reference signal EVM case, for the different modulation schemes shall not exceed the values specified in Table 6.4.2.1.3-1 for the parameters defined in Table 6.4.2.1.3-2 or Table 6.4.2.1.3-3 depending on UE power class. For EVM evaluation purposes, all 13 PRACH preamble formats and all 5 PUCCH formats are considered to have the same EVM requirement as QPSK modulated.

The measurement interval for the EVM determination is 10 subframes. The requirement is verified with the test metric of EVM (Link=TX beam peak direction, Meas=Link angle).

Table 6.4.2.1.3-1: Minim	um requirements for	or error vector magnitude
--------------------------	---------------------	---------------------------

Parameter	Unit	Average EVM level	Reference signal EVM level
Pi/2 BPSK	%	30.0	30.0
QPSK	%	17.5	17.5
16 QAM	%	12.5	12.5
64 QAM	%	8.0	8.0

# Table 6.4.2.1.3-2: Parameters for Error Vector Magnitude for power class 1

Parameter	Unit	Level
UE EIRP	dBm	≥ 4
UE EIRP for UL 16QAM	dBm	≥7
UE EIRP for UL 64QAM	dBm	≥ 11
Operating conditions		Normal conditions

# Table 6.4.2.1.3-3: Parameters for Error Vector Magnitude for power class 2, 3, and 4

Parameter	Unit	Level
UE EIRP	dBm	≥ -13
UE EIRP for UL 16QAM	dBm	≥ -10
UE EIRP for UL 64QAM	dBm	≥ -6
Operating conditions		Normal conditions

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4.2.1.

# 6.4.2.1.4 Test description

# 6.4.2.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 6.4.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Initial Conditions					
	Test Environment as specified in TS 38.508-1 Normal [10] subclause 4.1				
	iencies as specified in TS 38.508-1	Low range, Mid range, High range			
[10] subcla					
	nel Bandwidths as specified in TS	Lowest, Highest			
	10] subclause 4.3.1				
Test SCS a	as specified in Table 5.3.5-1	Lowest, Highest			
Test ID	Downlink Configuration		k Configuration		
Testib	N/A	Modulation	RB allocation (NOTE 1)		
	N/A				
1		DFT-s-OFDM PI/2 BPSK	Inner_Full for PC2, PC3 and PC4 Inner_Full_Region1 for PC1		
2		DFT-s-OFDM PI/2	Outer_Full		
		BPSK			
3		DFT-s-OFDM QPSK	Inner_Full for PC2, PC3 and PC4		
			Inner_Full_Region1 for PC1		
4		DFT-s-OFDM QPSK	Outer_Full		
5		DFT-s-OFDM 16 QAM	Inner_Full for PC2, PC3 and PC4		
			Inner_Full_Region1 for PC1		
6		DFT-s-OFDM 16 QAM	Outer_Full		
7		DFT-s-OFDM 64 QAM	Inner_Full for PC2, PC3 and PC4 Inner_Full_Region1 for PC1		
8		DFT-s-OFDM 64 QAM	Outer_Full		
9		CP-OFDM QPSK	Inner_Full for PC2, PC3 and PC4		
5			Inner_Full_Region1 for PC1		
10		CP-OFDM QPSK	Outer_Full		
11		CP-OFDM 16 QAM	Inner_Full for PC2, PC3 and PC4		
			Inner_Full_Region1 for PC1		
12		CP-OFDM 16 QAM	Outer_Full		
13		CP-OFDM 64 QAM	Inner_Full for PC2, PC3 and PC4		
			Inner_Full_Region1 for PC1		
14		CP-OFDM 64 QAM	Outer_Full		
	The specific configuration of each RB a 6.1-2 for PC1.	allocation is defined in Table	6.1-1 tor PC2, PC3 and PC4 or Table		
	Test Channel Bandwidths are checked	separately for each NR band	which applicable channel		
	bandwidths are specified in Table 5.3.5				

# Table 6.4.2.1.4.1-1: Test Configuration Table for PUSCH

Table 6.4.2.1.4.1-2: Test Configuration Table for PUCCH

Initial Conditions					
Test Environment as specified in TS 38.508-1		Normal			
[10] subc	lause 4.1				
	quencies as specified	in TS 38.508-1	See Table 6.4.2.1.4.1-1		
	lause 4.3.1				
Test Cha	nnel Bandwidths as	specified in TS	See Table 6.4.2.1.4.1-1		
38.508-1	[10] subclause 4.3.1				
Test SCS	as specified in Table	e 5.3.5-1	See Table 6.4.2.1.4.1-1		
		Т	est Parameters		
ID	Downlink Co	onfiguration	Uplink Configuration		
	Modulation	RB allocation	Waveform PUCCH format		
1	CP-OFDM QPSK	Full RB (Note 1)	CP-OFDM	PUCCH format = Format 1	
				Length in OFDM symbols = 14	
2	CP-OFDM QPSK	Full RB (Note 1)	DFT-s-OFDM	PUCCH format = Format 1	
	Length in OFDM symbols = 14				
NOTE 1:	NOTE 1: Full RB allocation shall be used per each SCS and channel BW as specified in Table 7.3.2.4.1-2.				
NOTE 2: Test Channel Bandwidths are checked separately for each NR band, which applicable channel bandwidths are specified in Table 5.3.5-1.					

Initial Conditions				
Test Environment as specified in TS 38.508-1	Normal			
[10] subclause 4.1				
Test Frequencies as specified in TS 38.508-1	See Table 6.4.2.1.4.1-1			
[10] subclause 4.3.1				
Test Channel Bandwidths as specified in TS	See Table 6.4.2.1.4.1-1			
38.508-1 [10] subclause 4.3.1				
Test SCS as specified in Table 5.3.5-1	See Table 6.4.2.1.4.1-1			
PRACH preamble format				
PRACH Configuration Index	52			
SS/PBCH SSS EPRE setting (dBm/120kHz)	-96			

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4.2.1.4.3

# 6.4.2.1.4.2 Test procedure

Test procedure for PUSCH:

- 1.1 Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
  - 1.2 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4.2.1.4.1-1. Since the UE has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
  - 1.3 Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
  - 1.4 Send continuously uplink power control "up" commands in the uplink scheduling information to the UE until the UE transmits at [P<sub>UMAX</sub> level]. Allow at least 200 ms starting from the first TPC command in this step for the UE to reach [P<sub>UMAX</sub> level]. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
  - 1.5 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
  - 1.6 Measure the EVM<sub> $\theta$ </sub>, EVM<sub> $\phi$ </sub>, EVM<sub>DMRS, $\theta$ </sub> and EVM<sub>DMRS, $\phi$ </sub> using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. For TDD, only slots consisting of only UL symbols are under test. Calculate  $\overline{EVM}_{DMRS} = min(\overline{EVM}_{DMRS,\theta}, \overline{EVM}_{DMRS,\phi})$  and  $EVM = min(EVM_{\theta}, EVM_{\phi})$ .
  - 1.7 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
  - NOTE1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4.2.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config without CP-OFDM condition. When switching to CP-OFDM waveform, send an NR RRCReconfiguration message with CP-OFDM condition.

NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Table 6.4.2.1.4.2-1: Void Table 6.4.2.1.4.2-2: Void

Table 6.4.2.1.4.2-3: Void

Test procedure for PUCCH:

- 2.1 Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2.2 PUCCH is set according to Table 6.4.2.1.4.1-2.
- 2.3 SS transmits PDSCH via PDCCH DCI format 0\_1 for C\_RNTI to transmit the DL RMC according to Table 6.4.2.1.4.1-2. The SS sends downlink MAC padding bits on the DL RMC. The transmission of PDSCH will make the UE send uplink ACK/NACK using PUCCH. There is no PUSCH transmission.
- 2.4 Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 2.5 SS send appropriate TPC commands for PUCCH to the UE until the UE transmit PUCCH at  $[P_{UMAX} \text{ level}]$ . Allow at least 200 ms starting from the first TPC command in this step for the UE to reach  $[P_{UMAX} \text{ level}]$ . Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 2.6 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 2.7 Measure PUCCH EVM<sub> $\theta$ </sub> and PUCCH EVM<sub> $\phi$ </sub> using Global In-Channel Tx-Test (Annex E). Calculate PUCCH EVM = min(PUCCH EVM<sub> $\theta$ </sub>, PUCCH EVM<sub> $\phi$ </sub>).
- 2.8 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4.2.1.4.1-2, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.
- NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Test procedure for PRACH:

- 3.1 Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 3.2 Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1.
- 3.3 The SS shall set RS EPRE according to Table 6.4.2.1.4.1-3.
- 3.4 PRACH is set according to Table 6.4.2.1.4.1-3.
- 3.5 The SS shall signal a Random Access Preamble ID via a PDCCH order to the UE and initiate a Non-contention based Random Access procedure.
- 3.6 The UE shall send the signalled preamble to the SS.
- 3.7 In response to the preamble, the SS shall transmit a random access response not corresponding to the transmitted random access preamble, or send no response.
- 3.8 The UE shall consider the random access response reception not successful then re-transmit the preamble with the calculated PRACH transmission power.

3.9 Repeat step 3.5 and 3.6 until the SS collect enough PRACH preambles ([2] preambles for format 0 and [10] preambles for format 4). Measure the  $EVM_{\theta}$  and  $EVM_{\phi}$  in PRACH channel using Global In-Channel Tx-Test (Annex E). Calculate  $EVM = min(EVM_{\theta}, EVM_{\phi})$ .

#### 6.4.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with the following exceptions for PRACH test.

#### Table 6.4.2.1.4.3-1: RACH-ConfigGeneric for PRACH test

Derivation Path: TS 38.508-1 [10], Table 4.6.3-130				
Information Element	Value/remark	Comment	Condition	
RACH-ConfigGeneric ::= SEQUENCE {				
preambleReceivedTargetPower	-60			
powerRampingStep	dB0			
}				

#### Table 6.4.2.1.4.3-2: ServingCellConfigCommon

Derivation Path: TS 38.508-1 [10], Table 4.6.3-168				
Information Element	Value/remark	Comment	Condition	
ServingCellConfigCommon ::= SEQUENCE {				
ss-PBCH-BlockPower	18			
}				

#### Table 6.4.2.1.4.3-3: ServingCellConfigCommonSIB

Derivation Path: TS 38.508-1 [10], Table 4.6.3-169				
Information Element Value/remark Comment Conditi				
ServingCellConfigCommonSIB ::= SEQUENCE {				
ss-PBCH-BlockPower	18			
}				

# 6.4.2.1.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4.2.1.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4.2.1.5-1 when embedded with data symbols of the respective modulation scheme.

The PUCCH EVM derived in Annex E.5.9.2 shall not exceed the values for QPSK in Table 6.4.2.1.5-1.

The PRACH EVM derived in Annex E.6.9.2 shall not exceed the values for QPSK in Table 6.4.2.1.5-1.

# Table 6.4.2.1.5-1: Test requirements for Error Vector Magnitude

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

# 6.4.2.2 Carrier leakage

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.

#### 6.4.2.2.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

#### 6.4.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

# 6.4.2.2.3 Minimum conformance requirements

Carrier leakage is an additive sinusoid waveform. The carrier leakage requirement is defined for each component carrier. The measurement interval is one slot in the time domain. The relative carrier leakage power is a power ratio of the additive sinusoid waveform to the power in the modulated waveform.

The requirement is verified with the test metric of Carrier Leakage (Link=TX beam peak direction, Meas=Link angle).

When carrier leakage is contained inside the spectrum confined within the configured UL and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4.2.2.3-1 for power class 1 UEs.

### Table 6.4.2.2.3-1: Minimum requirements for relative carrier leakage power for power class 1

Parameters	Relative Limit (dBc)
EIRP > 17 dBm	-25
4 dBm ≤ EIRP ≤ 17 dBm	-20

When carrier leakage is contained inside the spectrum occupied by the configured UL CCs and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4.2.2.3-2 for power class 2.

#### Table 6.4.2.2.3-2: Minimum requirements for relative carrier leakage power for power class 2

Parameters	Relative Limit (dBc)
EIRP > 6 dBm	-25
-13 dBm ≤ EIRP ≤ 6 dBm	-20

When carrier leakage is contained inside the spectrum occupied by the configured UL CCs and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4.2.2.3-3 for power class 3 UEs.

#### Table 6.4.2.2.3-3: Minimum requirements for relative carrier leakage power for power class 3

Parameters	Relative Limit (dBc)
EIRP > 0 dBm	-25
-13 dBm ≤ EIRP ≤ 0 dBm	-20

When carrier leakage is contained inside the spectrum occupied by the configured UL CCs and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4.2.2.3-4 for power class 4.

#### Table 6.4.2.2.3-4: Minimum requirements for relative carrier leakage power for power class 4

Parameters	Relative Limit (dBc)
EIRP > 11 dBm	-25
-13 dBm ≤ EIRP ≤11 dBm	-20

The normative reference for this requirement is TS 38.101-2[3] clause 6.4.2.2.

#### 6.4.2.2.4 Test description

#### 6.4.2.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 6.4.2.2.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Table 6.4.2.2.4.1-1	: Test C	Configuration
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Initial Conditions				
	est Environment as specified in TS 38.508-1 Normal			
[10] subcla	ause 4.1			
	uencies as specified in TS 38.508-1	Low range, Mid range, Hig	h range	
[10] subcla				
	nel Bandwidths as specified in TS	Mid		
	10] subclause 4.3.1			
Test SCS	as specified in Table 5.3.5-1	Lowest		
	Т	est Parameters		
Test ID	Downlink Configuration	Uplin	k Configuration	
	N/A	Modulation RB allocation (NOTE 1, 3)		
1		DFT-s-OFDM QPSK Inner_4RB_Left for PC2, PC3, PC4		
			Inner_16RB_Left_Region2 for PC1	
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.				
NOTE 2:	NOTE 2: Test Channel Bandwidths are checked separately for each NR band, which applicable channel			
bandwidths are specified in Table 5.3.5-1.				
NOTE 3: When the signalled DC carrier position is at Inner_4RB_Left for PC2, PC3, PC4, use Inner_4RB_Right				
NOTE 3:	When the signalled DC carrier position i			
NOTE 3:		d DC carrier position is in Inr		

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex [TBD], and uplink signals according to Annex [TBD].
- 4. The UL Reference Measurement channels are set according to Table 6.4.2.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4.2.2.4.3.

7. In case the parameter 3300 or 3301 is reported from the UE via *txDirectCurrentLocation* IE, do not proceed to test procedure and mark the test not applicable with reasoning in the test report.

#### 6.4.2.2.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4.2.2.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4.2.2.4.2-1 according to the power class.  $P_W$  is the power window according to Table 6.4.2.1.4.2-3 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 5. Measure carrier leakage using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 3
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

Table 6.4.2.2.4.2-1: UE EIRP Preq (dBm) for carrier leakage

#### Table 6.4.2.2.4.2-2: Power Window (dB) for carrier leakage

#### TBD

#### 6.4.2.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4.2.2.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

$$\operatorname{CarrLeak}_{\operatorname{Total}} = 10 \log_{10} \left( 10^{\operatorname{CarrLeak}_{\theta}/10} + 10^{\operatorname{CarrLeak}_{\phi}/10} \right), \text{ where}$$
$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1 and table 6.4.2.2.5-3 for power class 3. Allocated RBs are not under test.

Table 6.4.2.2.5-1: Test requirements for relative carrier leakage power for power class 1

LO Leakage		Parameters UE EIRP	Relative limit (dBc)	
		$17 + P_W dBm \pm P_W dB$	-25 + TT	
		4 + P <sub>w</sub> dBm ± P <sub>w</sub> dB	-20 + TT	
NOTE 1:	The n	neasurement bandwidth is 1 RB and	the limit is	
	expre	ssed as a ratio of measured power i	n one non-	
	alloca	ted RB to the measured total power	in all allocated	
	RBs.			
NOTE 2:	The a	The applicable frequencies for this limit are those that are		
	enclo	nclosed in the RBs containing the DC frequency if N <sub>RB</sub> is		
	odd, d	d, or in the two RBs immediately adjacent to the DC		
	freque	uency if N <sub>RB</sub> is even, but excluding any allocated RB.		
NOTE 3:	N <sub>RB</sub> is	is the Transmission Bandwidth Configuration (see Figure		
	5.3.3-	3-1).		
NOTE 4:	All po	power levels are UE EIRP in beam peak direction.		
NOTE 5:		s the power window according to Table 6.4.2.2.4.2-2 for carrier frequency f and the channel bandwidth BW.		

Table 6.4.2.2.5-2: Test requirements for relative carrier leakage power for power class 2

LO Leak	age	Parameters UE EIRP	Relative limit (dBc)	
		6 + Pw dBm ± Pw dB	-25 + TT	
		$-13 + P_W dBm \pm P_W dB$	-20 + TT	
NOTE 1:	The n	neasurement bandwidth is 1 RB and	the limit is	
	expre	ssed as a ratio of measured power i	n one non-	
	alloca	ted RB to the measured total power	in all allocated	
	RBs.			
NOTE 2:		The applicable frequencies for this limit are those that are		
	enclo	closed in the RBs containing the DC frequency if $N_{RB}$ is		
	odd, d	ld, or in the two RBs immediately adjacent to the DC		
	freque	uency if N <sub>RB</sub> is even, but excluding any allocated RB.		
NOTE 3:	N <sub>RB</sub> is	RB is the Transmission Bandwidth Configuration (see Figure		
	5.3.3-	1).		
NOTE 4:	All po	I power levels are UE EIRP in beam peak direction.		
NOTE 5:		Pw is the power window according to Table 6.4.2.2.4.2-2 for		
	the carrier frequency f and the channel bandwidth BW.		andwidth BW.	

LO Leakage		Parameters UE EIRP	Relative limit (dBc)		
		$0 + P_W dBm \pm P_W dB$	-25 + TT		
		$-13 + P_W dBm \pm P_W dB$	-20 + TT		
NOTE 1:	The n	neasurement bandwidth is 1 RB and	the limit is		
	expre	expressed as a ratio of measured power in one non-			
	alloca	ted RB to the measured total power	in all allocated		
	RBs.				
NOTE 2:	The a	The applicable frequencies for this limit are those that are			
	enclosed in the RBs containing the DC frequency if $N_{RB}$ is				
	odd, d	ld, or in the two RBs immediately adjacent to the DC			
	freque	equency if N <sub>RB</sub> is even, but excluding any allocated RB.			
NOTE 3:	N <sub>RB</sub> is	$I_{RB}$ is the Transmission Bandwidth Configuration (see Figure			
	5.3.3-	1).			
NOTE 4:	All po	All power levels are UE EIRP in beam peak direction.			
NOTE 5:	Pw is the power window according to Table 6.4.2.2.4.2-2 for				
	the carrier frequency f and the channel bandwidth BW.				

#### Table 6.4.2.2.5-3: Test requirements for relative carrier leakage power for power class 3

LO Leakage		Parameters UE EIRP	Relative limit (dBc)		
		11 + Pw dBm ± Pw dB	-25 + TT		
		$-13 + P_W dBm \pm P_W dB$	-20 + TT		
NOTE 1:	The m	neasurement bandwidth is 1 RB and	I the limit is		
	expressed as a ratio of measured power in one non-				
	alloca	ted RB to the measured total power	in all allocated		
	RBs.	RBs.			
NOTE 2:	The a	The applicable frequencies for this limit are those that are			
	enclos	enclosed in the RBs containing the DC frequency if $N_{RB}$ is			
	odd, c	d, or in the two RBs immediately adjacent to the DC			
	freque	uency if N <sub>RB</sub> is even, but excluding any allocated RB.			
NOTE 3:	N <sub>RB</sub> is	$_{\sf RB}$ is the Transmission Bandwidth Configuration (see Figure			
	5.3.3-	1).			
NOTE 4:	All power levels are UE EIRP in beam peak direction.				
NOTE 5:	Pw is the power window according to Table 6.4.2.2.4.2-2 for				
	the ca	arrier frequency f and the channel ba	andwidth BW.		

# 6.4.2.3 In-band emissions

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

# 6.4.2.3.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

6.4.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.4.2.3.3 Minimum conformance requirements

The in-band emission is defined as the average across 12 sub-carriers and as a function of the RB offset from the edge of the allocated UL transmission bandwidth. The in-band emission is measured as the ratio of the UE output power in a non–allocated RB to the UE output power in an allocated RB.

The basic in-band emissions measurement interval is identical to that of the EVM test.

The requirement is verified with the test metric of In-band emission (Link=TX beam peak direction, Meas=Link angle).

The relative in-band emission shall not exceed the values specified in Table 6.4.2.3.3-1 for power class 1 UEs.

The average of the in-band emission measurement over 10 sub-frames shall not exceed the values specified in Table 6.4.2.3.2-1 for power class 1, Table 6.4.2.3.3-2 for power class 2, Table 6.4.2.3.3-3 for power class 3 and Table 6.4.2.3.3-4 for power class 4 UEs.

Parameter description	Unit	Limit (NOTE 1)		Applicable Frequencies	
General	dB	7	Any non-allocated (NOTE 2)		
IQ Image	dB	-25	Output power > 27 dBm	Image frequencies	
Carrier	-	-20	Output power ≤ 27 dBm	(NOTES 2, 3)	
leakage	dBc	-25 -20	Output power > 17 dBm 4 dBm $\leq$ Output power $\leq$ 17 dBm	Carrier frequency (NOTES 4, 5)	
NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or					
<ul> <li>Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 10.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD</li> </ul>					
	NOTE 3: The applicable frequencies for this limit are those that are enclosed in the reflection of the allocated bandwidth, based on symmetry with respect to the carrier frequency, but excluding any allocated RBs.				
	NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.				
<ul> <li>NOTE 5: The applicable frequencies for this limit depend on the parameter <i>txDirectCurrentLocation</i> in <i>UplinkTxDirectCurrent</i> IE, and are those that are enclosed in the RBs containing the DC frequency but excluding any allocated RB.</li> </ul>					
NOTE 6: L <sub>CF</sub>	B is the Transmission Bandwidth (see Section 5.3).				
NOTE 7: N <sub>R</sub>	N <sub>RB</sub> is the Transmission Bandwidth Configuration (see Section 5.3).				
NOTE 8: EV	IOTE 8: EVM s the limit for the modulation format used in the allocated RBs.				
NOTE 9: $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or					
$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth).					
NOTE 10: P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.					
NOTE 11: All powers are EIRP in beam peak direction.					

The relative in-band emission shall not exceed the values specified in Table 6.4.2.3.3-2 for power class 2.

Parameter description	Unit	Limit (NOTE 1)	Applicable Frequencies	
General	dB	$max \begin{bmatrix} -25 - 10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) - 5.\frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix}$	Any non-allocated (NOTE 2)	
IQ Image	dB	-25         Output power > 16 dBm           -20         Output power ≤ 16 dBm	Image frequencies (NOTES 2, 3)	
Carrier leakage	dBc	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Carrier frequency (NOTES 4, 5)	
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 10.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD</li> <li>NOTE 3: The applicable frequencies for this limit are those that are enclosed in the reflection of the allocated bandwidth, based on symmetry with respect to the carrier frequency, but excluding any allocated RBs.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> </ul>				
<ul> <li>NOTE 5: The applicable frequencies for this limit depend on the parameter <i>txDirectCurrentLocation</i> in <i>UplinkTxDirectCurrent</i> IE, and are those that are enclosed in the RBs containing the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth (see Section 5.3).</li> <li>NOTE 7: N<sub>RB</sub> is the Transmission Bandwidth Configuration (see Section 5.3).</li> <li>NOTE 8: EVM s the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 9: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub>= 1 or Δ<sub>RB</sub>= -1 for the first adjacent RB outside of the allocated bandwidth).</li> <li>NOTE 10: P<sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.</li> </ul>				
NOTE 10. P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm. NOTE 11: All powers are EIRP in beam peak direction.				

# Table 6.4.2.3.3-2: Requirements for in-band emissions for power class 2

The relative in-band emission shall not exceed the values specified in Table 6.4.2.3.3-3 for power class 3 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General	dB	$max \begin{bmatrix} -25 - 10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) - 5.\frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix}$		Any non-allocated (NOTE 2)
IQ Image	dB	-25	Output power > 10 dBm	Image frequencies
Carrier		-20 -25	Output power ≤ 10 dBm Output power > 0 dBm	(NOTES 2, 3) Carrier frequency
leakage	dBc	-20	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)
			imit is evaluated in each non-allocated RB. For each such I	
			higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values	(General, IQ Image or
		akage) that apply. P <sub>RB</sub> is		
NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD				
NOTE 3: The applicable frequencies for this limit are those that are enclosed in the reflection of the allocated bandwidth, based on symmetry with respect to the carrier frequency, but excluding any allocated RBs.				
NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated				
RB to the measured total power in all allocated RBs.				
NOTE 5: The applicable frequencies for this limit depend on the parameter <i>txDirectCurrentLocation</i> in				
UplinkTxDirectCurrent IE, and are those that are enclosed in the RBs containing the DC frequency but excluding any allocated RB.				
NOTE 6: L <sub>CRB</sub> is the Transmission Bandwidth (see Section 5.3).				
NOTE 7: $N_{RB}$ is the Transmission Bandwidth Configuration (see Section 5.3).				
NOTE 8: EVM s the limit for the modulation format used in the allocated RBs.				
NOTE 9: $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or				
$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth).				
NOTE 10: P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.				
NOTE 11: All powers are EIRP in beam peak direction.				

# Table 6.4.2.3.3-3: Requirements for in-band emissions for power class 3

The relative in-band emission shall not exceed the values specified in Table 6.4.2.3.3-4 for power class 4 UEs.

Parameter Applicable Unit Limit (NOTE 1) description Frequencies  $max \begin{bmatrix} -25 & -10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) & -5.\frac{(|\Delta_{RB}|-1)}{L_{CRB}}, \\ & -55.1dBm - P_{RB} \end{bmatrix}$ Any non-allocated General dB (NOTE 2) Output power > 21 dBm -25 Image frequencies IQ Image dB Output power ≤ 21 dBm -20 (NOTES 2, 3) Carrier -25 Output power > 11 dBm Carrier frequency dBc -13 dBm ≤ Output power ≤11 dBm leakage -20 (NOTES 4, 5) NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub>- 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply.  $P_{RB}$  is defined in NOTE 10. NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD NOTE 3: The applicable frequencies for this limit are those that are enclosed in the reflection of the allocated bandwidth, based on symmetry with respect to the carrier frequency, but excluding any allocated RBs. NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs. NOTE 5: The applicable frequencies for this limit depend on the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE, and are those that are enclosed in the RBs containing the DC frequency but excluding any allocated RB. NOTE 6:  $L_{CRB}$  is the Transmission Bandwidth (see Section 5.3). NOTE 7:  $N_{PR}$  is the Transmission Bandwidth Configuration (see Section 5.3). NOTE 8: EVM s the limit for the modulation format used in the allocated RBs. NOTE 9:  $\Delta_{RB}$  is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g.  $\Delta_{RB}$  = 1 or  $\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth). NOTE 10: P<sub>RB</sub> is the transmitted power per allocated RB, measured in dBm. NOTE 11: All powers are EIRP in beam peak direction.

#### Table 6.4.2.3.3-4: Requirements for in-band emissions for power class 4

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The normative reference for this requirement is TS 38.101-2 [3] clause 6.4.2.3.

6.4.2.3.4 Test description

6.4.2.3.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 6.4.2.3.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex [TBD].

Initial Conditions					
Test Enviro [10] subcla	onment as specified in TS 38.508-1 use 4.1	Normal			
	encies as specified in TS 38.508-1	Low range, Mid range, Hig	h range		
Test Chan	nel Bandwidths as specified in TS 10] subclause 4.3.1	Lowest, Mid, Highest			
	as specified in Table 5.3.5-1	Lowest			
	Т	est Parameters			
Test ID	Downlink Configuration		k Configuration		
	N/A	Modulation	RB allocation (NOTE 1)		
1		DFT-s-OFDM PI/2 BPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
2		DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4		
			Inner_16RB_Right_Region2 for PC1		
3		CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
4		CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4		
			Inner_16RB_Right_Region2 for PC1		
	The specific configuration of each RB al 6.1-2 for PC1.				
	NOTE 2: Test Channel Bandwidths are checked separately for each NR band, which applicable channel bandwidths are specified in Table 5.3.5-1.				

# Table 6.4.2.3.4.1-1: Test Configuration Table for PUSCH

	Initial Conditions					
	Test Environment as specified in TS 38.508-1 See Table 6.4.2.3.4.1-1 [10] subclause 4.1					
	Test Frequencies as specified in TS 38.508-1See Table 6.4.2.3.4.1-1[10] subclause 4.3.1					
	Test Channel Bandwidths as specified in TSSee Table 6.4.2.3.4.1-138.508-1 [10] subclause 4.3.1See Table 6.4.2.3.4.1-1					
Test SCS	as specified in Table	e 5.3.5-1	See Table 6.4.2.3.4.1-1			
		Т	est Parameters			
ID	Downlink Co	onfiguration	Up	link Configuration		
	Modulation	RB allocation	Waveform	PUCCH format		
1	CP-OFDM QPSK	Full RB (Note 1)	CP-OFDM	PUCCH format = Format 1 Length in OFDM symbols = 14		
2	2 CP-OFDM QPSK Full RB (Note 1) DFT-s-OFDM PUCCH format = Format 1 Length in OFDM symbols = 14					
	Full RB allocation shall be used per each SCS and channel BW as specified in Table 7.3.2.4.1-2. Test Channel Bandwidths are checked separately for each NR band, which applicable channel bandwidths are specified in Table 5.3.5-1.					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex [TBD], and uplink signals according to Annex [TBD].
- 4. The UL Reference Measurement channels are set according to Table 6.4.2.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.

6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4.2.3.4.3

6.4.2.3.4.2 Test procedure

Test procedure for PUSCH:

- 1.1 Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
  - 1.2 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [1\_0] for C\_RNTI to schedule the UL RMC according to Table 6.4.2.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
  - 1.3 Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
  - 1.4 Send the appropriate TPC commands in the uplink scheduling information to the UE until UE output power is  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4.2.3.4.2-1 according to the power class with power ID = 1.  $P_W$  is the power window according to Table 6.4.2.3.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
  - 1.5 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
  - 1.6 Measure In-band emission  $IE_{\theta}$ ,  $IE_{\phi}$  using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. For TDD, only slots consisting of only UL symbols are under test. Calculate  $IE = IE_{\theta} + IE_{\phi}$ , where the calculation is based on linear power ratios.
  - 1.7 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
  - 1.8 Repeat steps 1.3 through 1.6 until In-band emissions have been measured for all power IDs in Table 6.4.2.1.4.2-1.
  - NOTE1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4.2.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config without CP-OFDM condition. When switching to CP-OFDM waveform, send an NR RRCReconfiguration message with CP-OFDM condition.
  - NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power ID	Unit	Level for power class 1	Level for power class 2	Level for power class 3	Level for power class 4
1	dBm	27	16	10	21
2	dBm	17	6	0	11

# Table 6.4.2.3.4.2-1: Parameters for In-band emissions

#### Table 6.4.2.3.4.2-2: Power Window (dB) for In-band emissions PUSCH and PUCCH

#### TBD

Test procedure for PUCCH:

- 2.1 Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2.2 PUCCH is set according to Table 6.4.2.3.4.1-2. SS transmits PDSCH via PDCCH DCI format [1A] for C\_RNTI to transmit the DL RMC according to Table 6.4.2.3.4.1-2. The SS sends downlink MAC padding bits on the DL RMC. The transmission of PDSCH will make the UE send uplink ACK/NACK using PUCCH.
- 2.3 Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.

- 2.4 Send the appropriate TPC commands in the uplink scheduling information for PUCCH to the UE until UE output power is  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4.2.3.4.2-1 according to the power class with power ID = 1. P<sub>W</sub> is the power window according to Table 6.4.2.3.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 2.5 SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 2.6 Measure In-band emission  $IE_{\theta}$ ,  $IE_{\phi}$  using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. Calculate  $IE = IE_{\theta} + IE_{\phi}$ , where the calculation is based on linear power ratios.
- 2.7 SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 2.8 Repeat steps 2.3 through 2.6 until In-band emissions have been measured for all power IDs in Table 6.4.2.1.4.2-1.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

# 6.4.2.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4.2.3.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4.2.3.5-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies	
General (NOTE 12)	dB	ma.	$ \begin{pmatrix} -25 - 10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) - 5.\frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{pmatrix} + TT $	Any non-allocated (NOTE 2)	
IQ Image (NOTE 12)	dB	-25+TT -20+TT	Output power > 27 dBm Output power ≤ 27 dBm	Image frequencies (NOTES 2, 3)	
Carrier leakage (NOTE 12)	dBc	-25+TT -20+TT	Output power > 17 dBm 4 dBm ≤ Output power ≤ 17 dBm	Carrier frequency (NOTES 4, 5)	
NOTE 1: An rec	quireme	ent is calculated as the h	imit is evaluated in each non-allocated RB. For each such higher of ( <i>P<sub>RB</sub></i> - 25 dB) and the power sum of all limit values defined in NOTE 10		
NOTE 2: Th RE pi/ the NOTE 3: Th ba NOTE 4: Th RE NOTE 5: Th <i>Up</i> alle	RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD				
		e Transmission Bandwid			
NOTE 8: EV	<ul> <li>TE 7: N<sub>RB</sub> is the Transmission Bandwidth Configuration (see Section 5.3).</li> <li>TE 8: EVM s the limit for the modulation format used in the allocated RBs.</li> </ul>				
	NOTE 9: $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or $\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth).				
NOTE 10: P <sub>R</sub>	<sub>B</sub> is the	transmitted power per a	allocated RB, measured in dBm.		
NOTE 12: In	NOTE 11: All powers are EIRP in beam peak direction. NOTE 12: In case the parameter 3300 or 3301 is reported from UE via <i>txDirectCurrentLocation</i> IE, IQ Image and Carrier leakage limit do not apply and General limit applies for all non-allocated frequencies.				

# Table 6.4.2.3.5-1: Test requirements for in-band emissions for power class 1

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4.2.3.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies	
General (NOTE 12)	dB	$max \begin{bmatrix} -25 - 10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) - 5.\frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix} + TT$		Any non-allocated (NOTE 2)	
IQ Image (NOTE 12)	dB	-25 + TT -20 + TT	Output power > 16 dBm Output power ≤ 16 dBm	Image frequencies (NOTES 2, 3)	
Carrier leakage (NOTE 12)	dBc	-25 + TT -20 + TT	Output power > 6 dBm -13 dBm ≤ Output power ≤ 6 dBm	Carrier frequency (NOTES 4, 5)	
NOTE 2: The RB pi/2 the NOTE 3: The bas NOTE 4: The RB NOTE 5: The Up in t NOTE 6: L <sub>CF</sub> NOTE 6: L <sub>CF</sub> NOTE 7: N <sub>RI</sub> NOTE 8: EV	<ul> <li>RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD</li> <li>NOTE 3: The applicable frequencies for this limit are those that are enclosed in the reflection of the allocated bandwidth, based on symmetry with respect to the carrier frequency, but excluding any allocated RBs.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit depend on the parameter <i>txDirectCurrentLocation</i> in <i>UplinkTxDirectCurrent</i> IE, and are those that are enclosed in the RBs containing the DC frequency if N<sub>RB</sub> is odd, or in the two RBs immediately adjacent to the DC frequency if N<sub>RB</sub> is even but excluding any allocated RB.</li> </ul>				
Δ <sub>RE</sub> NOTE 10: P <sub>RE</sub> NOTE 11: All NOTE 12: In o	<sub>3</sub> = -1 fo <sub>3</sub> is the powers case th	r the first adjacent RB o transmitted power per a s are EIRP in beam pea e parameter 3300 or 33	et between the allocated RB and the measured non-allocate outside of the allocated bandwidth). allocated RB, measured in dBm. k direction. 601 is reported from UE via <i>txDirectCurrentLocation</i> IE, IQ I eneral limit applies for all non-allocated frequencies.		

# Table 6.4.2.3.5-2: Test requirements for in-band emissions for power class 2

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4.2.3.5-3 for power class 3 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General (NOTE 12)	dB	$max \begin{bmatrix} -25 - 10.10\\ 20.\log_{10}(\text{EVM}) - \\ -55.1dBn \end{bmatrix}$	$-5.\frac{( \Delta_{RB} -1)}{L_{CRB}}, + TT$	Any non-allocated (NOTE 2)
IQ Image (NOTE 12)	dB	-25+TT -20+TT	Output power > 10 dBm Output power ≤ 10 dBm	Image frequencies (NOTES 2, 3)
Carrier		-25+TT	Output power > 0 dBm	Carrier frequency
leakage (NOTE 12)	dBc	-20+TT	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)
Ca	rrier lea	akage) that apply. P <sub>RB</sub> is	higher of ( <i>P<sub>RB</sub></i> - 25 dB) and the power sum of all limit val s defined in NOTE 10. RB and the limit is expressed as a ratio of measured p	
RE pi//	8 to the 2 BPSk	measured average pow	ver per allocated RB, where the averaging is done acros g, the limit is expressed as a ratio of measured power in ted RB with highest PSD.	ss all allocated RBs. For
			is limit are those that are enclosed in the reflection of th to the carrier frequency, but excluding any allocated RE	
		urement bandwidth is 1 measured total power i	RB and the limit is expressed as a ratio of measured p n all allocated RBs.	ower in one non-allocate
Up		DirectCurrent IE, and are	is limit depend on the parameter <i>txDirectCurrentLocatic</i> e those that are enclosed in the RBs containing the DC	
NOTE 6: L <sub>cr</sub>	<sub>RB</sub> is the	Transmission Bandwid	dth (see Section 5.3).	
NOTE 7: N <sub>R</sub>	<sub>в</sub> is the	Transmission Bandwid	th Configuration (see Section 5.3).	
NOTE 8: EV	'M s the	limit for the modulatior	n format used in the allocated RBs.	
NOTE 9: $\Delta_R$	<sub>B</sub> is the	starting frequency offse	et between the allocated RB and the measured non-allo	cated RB (e.g. $\Delta_{\rm RB}$ = 1 or
•	<sub>B</sub> = -1 fo	r the first adjacent RB c	outside of the allocated bandwidth).	
$\Delta_{R}$	ic the	transmitted power per a	allocated RB, measured in dBm.	
	BISTIL			
NOTE 10: P <sub>R</sub> NOTE 11: All	powers	are EIRP in beam pea		

# Table 6.4.2.3.5-3: Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4.2.3.5-4 for power class 4 UEs.

Parameter Unit Limit (NOTE 1) Applicable				
description	Unit		Limit (NOTE 1)	Frequencies
General (NOTE 12)	dB		$ x \begin{bmatrix} -25 - 10.\log_{10}\left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20.\log_{10}(EVM) - 5.\frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix} + TT $	Any non-allocated (NOTE 2)
IQ Image	dB	-25 + TT	Output power > 21 dBm	Image frequencies
(NOTE 12) Carrier	-	-20 + TT	Output power ≤ 21 dBm	(NOTES 2, 3)
leakage (NOTE 12)	dBc	-25 + TT -20 + TT	Output power > 11 dBm -13 dBm ≤ Output power ≤11 dBm	Carrier frequency (NOTES 4, 5)
NOTE 1: An			imit is evaluated in each non-allocated RB. For each such higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values	
Ca	rrier lea	akage) that apply. P <sub>RB</sub> is	s defined in NOTE 10.	
RE pi/: the	8 to the 2 BPSK e measu	measured average pow ( with Spectrum Shapin ured power in the alloca	RB and the limit is expressed as a ratio of measured pow- ver per allocated RB, where the averaging is done across a g, the limit is expressed as a ratio of measured power in or ted RB with highest PSD	all allocated RBs. For the non-allocated RB to
		-	is limit are those that are enclosed in the reflection of the a to the carrier frequency, but excluding any allocated RBs.	llocated bandwidth,
		urement bandwidth is 1 measured total power i	RB and the limit is expressed as a ratio of measured pown n all allocated RBs.	er in one non-allocated
NOTE 5: The applicable frequencies for this limit depend on the parameter <i>txDirectCurrentLocation</i> in <i>UplinkTxDirectCurrent</i> IE, and are those that are enclosed in the RBs containing the DC frequency but excluding any allocated RB.				
NOTE 6: L <sub>CI</sub>	<sub>RB</sub> is the	e Transmission Bandwid	dth (see Section 5.3).	
			th Configuration (see Section 5.3).	
			n format used in the allocated RBs.	
			et between the allocated RB and the measured non-allocated	ed RB (e.g. $\Delta_{RB}$ = 1 or
	-		outside of the allocated bandwidth).	
			allocated RB, measured in dBm.	
		are EIRP in beam pea		
			801 is reported from UE via <i>txDirectCurrentLocation</i> IE, IQ I eneral limit applies for all non-allocated frequencies.	Image and Carrier

# Table 6.4.2.3.5-4: Test requirements for in-band emissions for power class 4

# 6.4.2.4 EVM equalizer spectrum flatness

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

# Measurement Uncertainty and Test Tolerance are FFS.

# 6.4.2.4.1 Test purpose

The zero-forcing equalizer correction applied in the EVM measurement process (as described in Annex E) must meet a spectral flatness requirement for the EVM measurement to be valid. The EVM equalizer spectrum flatness is defined in terms of the maximum peak-to-peak ripple of the equalizer coefficients (dB) across the allocated uplink block, at which the equalizer coefficients are generated by the EVM measurement process. The basic measurement interval is the same as for EVM.

The EVM equalizer spectrum flatness requirement does not limit the correction applied to the signal in the EVM measurement process but for the EVM result to be valid, the equalizer correction that was applied must meet the EVM equalizer spectrum flatness minimum requirements.

# 6.4.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

# 6.4.2.4.3 Minimum conformance requirements

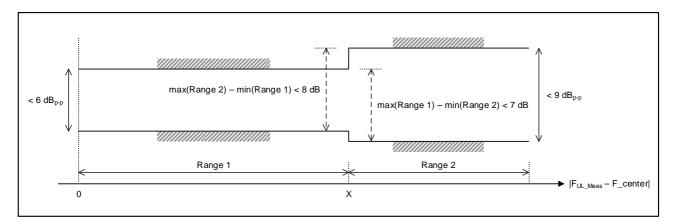
For pi/2 BPSK modulation, the minimum requirements are defined in Clause 6.4.2.5.3.

The peak-to-peak variation of the EVM equalizer coefficients contained within the frequency range of the uplink allocation shall not exceed the maximum ripple specified in Table 6.4.2.4.3-1 for normal conditions. For uplink allocations contained within both Range 1 and Range 2, the coefficients evaluated within each of these frequency ranges shall meet the corresponding ripple requirement and the following additional requirements: the relative difference between the maximum coefficient in Range 1 and the minimum coefficient in Range 2 (Table 6.4.2.4.3-1) must not be larger than 7 dB, and the relative difference between the maximum coefficient in Range 2 and the minimum coefficient in Range 1 must not be larger than 8 dB (see Figure 6.4.2.4.3-1).

The requirement is verified with the test metric of EVM SF (Link=TX beam peak direction, Meas=Link angle).

# Table 6.4.2.4.3-1: Minimum requirements for EVM equalizer spectrum flatness (normal conditions)

	Frequency range	Maximum ripple (dB)
	F <sub>UL_Meas</sub> – F <sub>center</sub>   ≤ X MHz	6 (p-p)
	(Range 1)	
	9 (p-p)	
	(Range 2)	
NOTE 1:	FUL_Meas refers to the sub-carrier frequency for which evaluated	the equalizer coefficient is
	F <sub>center</sub> refers to the center frequency of the CC X, in MHz, is equal to 30% of the CC bandwidth	



# Figure 6.4.2.4.3-1: The limits for EVM equalizer spectral flatness with the maximum allowed variation of the coefficients indicated under normal conditions

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4.2.4.

6.4.2.4.4 Test description

# 6.4.2.4.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 6.4.2.4.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex [TBD].

Initial Conditions					
Test Enviro [10] subcla	onment as specified in TS 38.508-1 ause 4.1	Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1		Low range, Mid range, High	n range		
	nel Bandwidths as specified in TS 10] subclause 4.3.1	Lowest, Mid, Highest			
Test SCS	as specified in Table 5.3.5-1	Lowest			
	Test Parameters				
Test ID	Downlink Configuration	Uplink	Configuration		
	N/A	Modulation	RB allocation (NOTE 1)		
1		DFT-s-OFDM QPSK	Outer_Full		
2		CP-OFDM QPSK	Outer_Full		
<ul> <li>NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.</li> <li>NOTE 2: Test Channel Bandwidths are checked separately for each NR band, which applicable channel bandwidths are specified in Table 5.3.5-1.</li> </ul>					

# Table 6.4.2.4.4.1-1: Test Configuration

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.1.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex [TBD], and uplink signals according to Annex [TBD].
- 4. The UL Reference Measurement channels are set according to Table 6.4.2.4.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4.2.4.3

#### 6.4.2.4.4.2 Test procedure

- 1. Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.4.2.4.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC
- 3. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 4. Send continuously uplink power control "up" commands in the uplink scheduling information to the UE until the UE transmits at P<sub>UMAX</sub> level. Allow at least 200 ms for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 5. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 6. Measure spectrum flatness using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. For TDD, only slots consisting of only UL symbols are under test.
- 7. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4.2.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config without CP-OFDM condition. When switching to CP-OFDM waveform, send an NR RRCReconfiguration message with CP-OFDM condition.

NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

# 6.4.2.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4.2.4.5 Test requirement

Each of the *n* spectrum flatness functions, shall derive four ripple results in Annex E.4.4. The derived results shall not exceed the values in Figure 6.4.2.4.5-1: The peak-to-peak variation of the EVM equalizer coefficients contained within the frequency range of the uplink allocation shall not exceed the maximum ripple specified in Table 6.4.2.4.5-1 for normal conditions. For uplink allocations contained within both Range 1 and Range 2, the coefficients evaluated within each of these frequency ranges shall meet the corresponding ripple requirement and the following additional requirements: the relative difference between the maximum coefficient in Range 1 and the minimum coefficient in Range 2 (Table 6.4.2.4.5-1) must not be larger than 7 dB + TT, and the relative difference between the maximum coefficient in Range 1 must not be larger than 8 dB + TT (see Figure 6.4.2.4.5-1).

The UE passes the test when the derived results for at least one polarization fulfil the test requirements.

# Table 6.4.2.4.5-1: Test requirements for EVM equalizer spectrum flatness (normal conditions)

	Frequency range	Maximum ripple (dB)		
	F <sub>UL_Meas</sub> – F <sub>center</sub>   ≤ X MHz	6 +TT (p-p)		
	(Range 1)			
	F <sub>UL_Meas</sub> – F <sub>center</sub>   > X MHz 9 + TT (p-p)			
	(Range 2)			
NOTE 1:	$F_{\text{UL}\_\text{Meas}}$ refers to the sub-carrier frequency for which evaluated	the equalizer coefficient is		
NOTE 2:	NOTE 2: F <sub>center</sub> refers to the center frequency of the CC			
NOTE 3:	X, in MHz, is equal to 30% of the CC bandwidth			

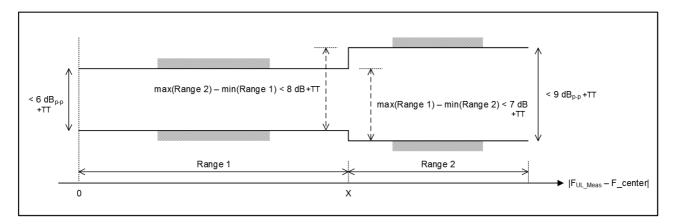


Figure 6.4.2.4.5-1: The limits for EVM equalizer spectral flatness with the maximum allowed variation of the coefficients indicated under normal conditions

# 6.4.2.5 EVM spectral flatness for pi/2 BPSK modulation

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Whether and, if yes, how to test the requirement on shaping filter is FFS.

#### 6.4.2.5.1 Test purpose

Same test purpose as in clause 6.4.2.4.1.

#### 6.4.2.5.2 Test applicability

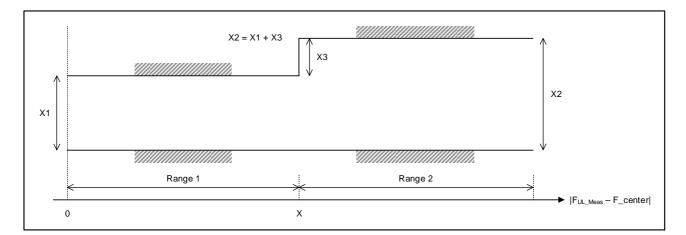
This test case applies to all types of NR UE release 15 and forward.

#### 6.4.2.5.3 Minimum conformance requirements

These requirements are defined for pi/2 BPSK modulation. The EVM equalizer coefficients across the allocated uplink block shall be modified to fit inside the mask specified in Table 6.4.2.5.3-1 for normal conditions, prior to the calculation of EVM. The limiting mask shall be placed to minimize the change in equalizer coefficients in a sum of squares sense.

Table 6.4.2.5.3-1: Mask for EVM equalizer coefficients for pi/2 BPSK (normal conditions)

Frequency range	Parameter	Maximum ripple (dB)			
F <sub>UL_Meas</sub> – F <sub>center</sub>   ≤ X MHz	X1	6 (p-p)			
(Range 1)					
F <sub>UL_Meas</sub> – F <sub>center</sub>   > X MHz	X2	14 (p-p)			
(Range 2)					
NOTE 1: F <sub>UL Meas</sub> refers to the sub-carrier frequency for which the equalizer coefficient is evaluated.					
NOTE 2: F <sub>center</sub> refers to the centre frequency of an allocated block of PRBs.					
NOTE 3: X, in MHz, is equal to 25% of the bandwidth of the PRB allocation.					
NOTE 4: See Figure 6.4.2.5-1 for description of X1, X2 and X	3.				



# Figure 6.4.2.5.3-1: The limits for EVM equalizer spectral flatness with the maximum allowed variation. F<sub>center</sub> denotes the centre frequency of the allocated block of PRBs. F\_alloc denotes the bandwidth of the PRB allocation

This requirement does not apply to other modulation types. The UE shall be allowed to employ spectral shaping for pi/2 BPSK. The shaping filter shall be restricted so that the impulse response of the transmit chain shall meet

$$\left| \tilde{a}_{t}(t,0) \right| \geq \left| \tilde{a}_{t}(t,\tau) \right| \quad \forall \tau \neq 0$$

$$20 \log_{10} | \tilde{a}_t(t,\tau) | < -15 \text{ dB} \quad 1 < \tau < \text{M} - 1,$$

Where:

 $|\tilde{a}_t(t,\tau)| = IDFT\{ |\tilde{a}_t(t,f)| e^{j\phi(t,f)} \},$ 

f is the frequency of the M allocated subcarriers,

 $\tilde{a}(t,f)$  and  $\varphi(t,f)$  are the amplitude and phase response, respectively of the transmit chain

0dB reference is defined as  $20\log_{10} | \tilde{a}_t(t,0) |$ 

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4.2.5.

# 6.4.2.5.4 Test description

6.4.2.5.4.1 Initial condition

Same initial conditions as in clause 6.4.2.4.4.1 with following exceptions:

- Instead of Table 6.4.2.4.4.1-1 → use Table 6.4.2.5.4.1-1

# Table 6.4.2.5.4.1-1: Test Configuration

	Initial Conditions					
Test Enviro [10] subcla	onment as specified in TS 38.508-1 luse 4.1	Normal				
Test Frequ [10] subcla	iencies as specified in TS 38.508-1 iuse 4.3.1	Low range, Mid range, High range				
	Test Channel Bandwidths as specified in TS Lowest, Mid, Highest 38.508-1 [10] subclause 4.3.1					
Test SCS as specified in TS 38.508-1 [10]     Lowest       subclause [TBD]     Lowest						
		est Parameters				
Test ID	Downlink Configuration	Uplink	Configuration			
	N/A	Modulation	RB allocation (NOTE 1)			
1		DFT-s-OFDM pi/2-BPSK	Outer_Full			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						
	NOTE 2: Test Channel Bandwidths are checked separately for each NR band, which applicable channel bandwidths are specified in Table 5.3.5-1.					

# 6.4.2.5.4.2 Test procedure

- 1. Retrieve the LO position from the parameter txDirecCurrentLocation in UplinkTxDirectCurrent IE.
- 2. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.4.2.5.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC
- 3. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. Send continuously uplink power control "up" commands in the uplink scheduling information to the UE until the UE transmits at P<sub>UMAX</sub> level. Allow at least 200 ms for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 5. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 6. Measure spectrum flatness using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. For TDD, only slots consisting of only UL symbols are under test.
- 7. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

# 6.4.2.5.4.3 Message contents

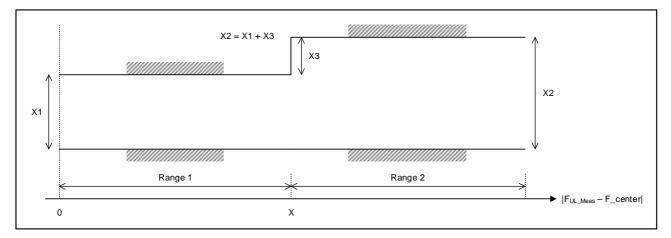
Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4.2.5.5 Test requirement

Each of the *n* spectrum flatness functions, shall derive four ripple results in Annex E.4.4. The derived results shall not exceed the values in Table 6.4.2.5.5-1 and Figure 6.4.2.5.5-1:

Table 6.4.2.5.5-1: Test requirement for EVM equalizer coefficients for pi/2 BPSK (normal conditions)

Frequency range	Parameter	Maximum ripple (dB)		
F <sub>UL_Meas</sub> – F <sub>center</sub>   ≤ X MHz	X1	6 + TT (p-p)		
(Range 1)				
F <sub>UL_Meas</sub> – F <sub>center</sub>   > X MHz	X2	14 + TT (p-p)		
(Range 2)				
NOTE 1: FUL_Meas refers to the sub-carrier frequency for which	the equalizer of	coefficient is evaluated.		
NOTE 2: F <sub>center</sub> refers to the centre frequency of an allocated block of PRBs.				
NOTE 3: X, in MHz, is equal to 25% of the bandwidth of the PRB allocation.				
NOTE 4: See Figure 6.4.2.5-1 for description of X1, X2 and X	3.			



# Figure 6.4.2.5.5-1: The limits for EVM equalizer spectral flatness with the maximum allowed variation. $F_{center}$ denotes the centre frequency of the allocated block of PRBs

The UE passes the test when the derived results for at least one polarization fulfil the test requirements.

# 6.4A Transmit signal quality for CA

# 6.4A.1 Frequency error for CA

# 6.4A.1.0 Minimum conformance requirements

The requirements in this clause apply to UEs of all power classes.

For intra-band contiguous carrier aggregation, the UE basic measurement interval of modulated carrier frequency is 1 UL slot. The mean value of basic measurements of UE modulated carrier frequencies per band shall be accurate to within  $\pm 0.1$  PPM observed over a period of 1ms of cumulated measurement intervals compared to the carrier frequency of primary component carrier received from the gNB.

The frequency error is defined as a directional requirement. The requirement is verified in beam locked mode on beam peak direction.

# 6.4A.1.1 Frequency error for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

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- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Point with SCC allocation is FFS

## 6.4A.1.1.1 Test purpose

This test verifies the ability of both, the receiver and the transmitter, to process frequency correctly.

Receiver: to extract the correct frequency from the stimulus signal, offered by the System simulator, under ideal propagation conditions and low level.

Transmitter: to derive the correct modulated carrier frequency from the results, gained by the receiver.

# 6.4A.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

# 6.4A.1.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.1.0.

# 6.4A.1.1.4 Test description

# 6.4A.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.4A.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.1.1.4.1-1: Test Configuration Table

			Default Cor	nditions				
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]						Normal		
Test Frequ	lencies as speci	fied in TS 38.508-	-1 [10] subclause		Mid ran	ge		
[4.3.1.2.3]	for different CA	bandwidth classe	S					
		ing (aggregated B				t aggregated BW of	the CA	
		.1-1 for the CA Co		S	configu	ration		
		ts supported by th	ie UE					
Test SCS	as specified in T	able 5.3.5-1			Lowest			
			Test Para					
CA Cor	figuration / Ag	gregated BW	Downlink (	Configurati	ion Uplink Configuration			
Test ID	& 33	CBW (MHz)	Modulation	RB allo	cation	Modulation	RB allocation	
	Mapping						(NOTE 1)	
	(NOTE 4)							
	PCC/CC1	Default	CP-OFDM	Full RB (	(NOTE	DFT-s-OFDM	REFSENS	
1			QPSK	1)		QPSK	(NOTE 2)	
	SCC/CC2							
						ecified in Table 7.3.		
NOTE 2:	NOTE 2: REFSENS refers to Table 7.3.2.4.1-3 which defines uplink RB configuration and start RB location for each							
	SCS, channel E	W and NR band.						

1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.

2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.

- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.1.1.4.3

6.4A.1.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause [TBD]. Message contents are defined in clause 6.4A.1.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [x], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS transmits PDSCH via PDCCH DCI format 1\_0 for C\_RNTI to transmit the DL RMC according to Table 6.4.1.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 5. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 6. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. Send continuously uplink power control "up" commands to the UE in every uplink scheduling information to the UE so that the UE transmits at P<sub>UMAX</sub> level for the duration of the test. Allow at least 200ms starting from the first TPC Command for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.6.Measure the Frequency Error using Global In-Channel Tx-Test (Annex E) for the θ- and φ-polarization. For TDD, only slots consisting of only UL symbols are under test.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.4A.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4A.1.1.5 Test Requirements

The 10 frequency error  $\Delta f$  results for the  $\theta$ -polarization or the *n* frequency error  $\Delta f$  results for the  $\varphi$ -polarization must fulfil the test requirement:

 $|\Delta f| \le (0.1 \text{ PPM} + 0.005 \text{ PPM}), \text{ (for Aggregated BW } \le 400 \text{MHz})$ 

# 6.4A.1.2 Frequency error for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Point with SCC allocation is FFS

#### - How to apply Multi-band relaxation into UL CA test cases is FFS.

#### 6.4A.1.2.1 Test purpose

This test verifies the ability of both, the receiver and the transmitter, to process frequency correctly.

Receiver: to extract the correct frequency from the stimulus signal, offered by the System simulator, under ideal propagation conditions and low level.

Transmitter: to derive the correct modulated carrier frequency from the results, gained by the receiver.

# 6.4A.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

6.4A.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.1.0.

# 6.4A.1.2.4 Test description

Same as in clause 6.4A.1.1.4 with following exceptions:

- Instead of Table 6.4A.1.1.4.1-1 $\rightarrow$  use Table 6.4A.1.2.4.1-1.
- Instead of clause 6.4A.1.1.4.3  $\rightarrow$  use clause 6.4A.1.2.4.3.
- Instead of Table 6.4A.1.1.5-1 $\rightarrow$  use Table 6.4A.1.2.5-1.

# Table 6.4A.1.2.4.1-1: Test Configuration Table

			Default Cor	nditions			
Test Envir	onment as spec	ified in TS 38.508	Normal				
		ified in TS 38.508			Mid ran	ge	
[4.3.1.2.3]	for different CA	bandwidth classe	S			-	
		ing (aggregated B			Highest	t aggregated BW of	the CA
		.1-1 for the CA Co		S	configu	ration	
		ts supported by th	ne UE				
Test SCS	as specified in T	able 5.3.5-1			Lowest		
			Test Para	meters			
CA Cor	figuration / Ag		Downlink (				nfiguration
Test ID	CC &	CBW (MHz)	Modulation	RB allo	cation	Modulation	RB allocation
	Mapping						(NOTE 1)
	(NOTE 4)						
	PCC/CC1	default	CP-OFDM	Full RB (	NOTE	DFT-s-OFDM	REFSENS
1		default	CP-OFDM QPSK	Full RB ( 1)	NOTE	DFT-s-OFDM QPSK	REFSENS (NOTE 2)
1		default		Full RB ( 1)	NOTE		
1	PCC/CC1	default		Full RB ( 1) -	NOTE		
	PCC/CC1 SCC/CC2 SCC/CC3 Full RB allocatio	on shall be used p	QPSK - - per each SCS and	1) - - - 	W as spe	QPSK - - ecified in Table 7.3.	(NOTE 2) - - 2.4.1-2.
	PCC/CC1 SCC/CC2 SCC/CC3 Full RB allocatio	on shall be used p	QPSK - - per each SCS and	1) - - - 	W as spe	QPSK - -	(NOTE 2) - 2.4.1-2.

# 6.4A.1.2.5 Test Requirements

The 10 frequency error  $\Delta f$  results for the  $\theta$ -polarization or the *n* frequency error  $\Delta f$  results for the  $\varphi$ -polarization must fulfil the test requirement:

 $|\Delta f| \leq (0.1 \text{ PPM} + 0.005 \text{ PPM}), \text{ (for Aggregated BW } \leq 400 \text{MHz})$ 

# 6.4A.1.3 Frequency error for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

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- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- Test Point with SCC allocation is FFS

# 6.4A.1.3.1 Test purpose

This test verifies the ability of both, the receiver and the transmitter, to process frequency correctly.

Receiver: to extract the correct frequency from the stimulus signal, offered by the System simulator, under ideal propagation conditions and low level.

Transmitter: to derive the correct modulated carrier frequency from the results, gained by the receiver.

# 6.4A.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

# 6.4A.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.1.0.

# 6.4A.1.3.4 Test description

Same as in clause 6.4A.1.1.4 with following exceptions:

- Instead of Table 6.4A.1.1.4.1-1  $\rightarrow$  use Table 6.4A.1.3.4.1-1.
- Instead of clause 6.4A.1.1.4.3  $\rightarrow$  use clause 6.4A.1.3.4.3.
- Instead of Table 6.4A.1.1.5-1 $\rightarrow$  use Table 6.4A.1.3.5-1.

# Table 6.4A.1.3.4.1-1: Test Configuration Table

			Default Cor	nditions			
Test Envir	onment as spec	ified in TS 38.508	-1 [10] subclause	[4.1]	Norma		
			-1 [10] subclause		Mid rar	ige	
[4.3.1.2.3]	for different CA	bandwidth classe	S				
			SW of the CA conf		Highes	t aggregated BW of	the CA
			onfiguration acros	S	configu	ration	
		ts supported by th	ne UE				
Test SCS	as specified in T	able 5.3.5-1			Lowest		
			Test Para				
CA Con	figuration / Ag	gregated BW	Downlink (	Configurati	on	Uplink Cor	nfiguration
Test ID	& CC	CBW (MHz)	Modulation	RB allo	cation	Modulation	RB allocation
	Mapping						(NOTE 1)
	(NOTE 4)				NOTE	DET OFDM	DEFORMO
	PCC/CC1	Default	CP-OFDM	Full RB (	NOTE	DFT-s-OFDM	REFSENS
	000/000		QPSK	1)		QPSK	(NOTE 2)
1	SCC/CC2		-	-		-	-
	SCC/CC3		-	-		-	-
	SCC/CC4		-	-		-	-
						ecified in Table 7.3.	
NOTE 2:			1.1-3 which define	s uplink RE	8 configu	ration and start RB	location for each
	SCS, channel E	W and NR band.					

# 6.4A.1.3.5 Test Requirements

The 10 frequency error  $\Delta f$  results for the  $\theta$ -polarization or the *n* frequency error  $\Delta f$  results for the  $\varphi$ -polarization must fulfil the test requirement:

 $|\Delta f| \le (0.1 \text{ PPM} + 0.005 \text{ PPM}), \text{ (for Aggregated BW} \le 400 \text{MHz})$ 

# 6.4A.2 Transmit modulation quality for CA

# 6.4A.2.0 General

For intra-band contiguous carrier aggregation, the requirements in subclauses 6.4A.2.1.0, 6.4A.2.2.0, and 6.4A.2.3.0.

All the parameters defined in subclause 6.4A.2 are defined using the measurement methodology specified in Annex E.

All the requirements in 6.4A.2 are defined as directional requirement. The requirements are verified in beam locked mode on beam peak direction, with both UL polarizations active.

In case the parameter 3300 or 3301 is reported from UE via *txDirectCurrentLocation* IE (as defined in TS 38.331 [13]), carrier leakage measurement requirement in subclause 6.4A.2.2.0 and 6.4A.2.3.0 shall be waived, and the RF correction with regard to the carrier leakage and IQ image shall be omitted during the calculation of transmit modulation quality.

The UE is defined to be configured for CA operation when it has at least one of UL or DL configured for CA.

# 6.4A.2.1 Error vector magnitude for CA

# 6.4A.2.1.0 Minimum conformance requirements

The requirements in this subclause apply to UEs of all power classes. For intra-band contiguous carrier aggregation, the Error Vector Magnitude requirement of section 6.4.2.1 is defined for each component carrier. Requirements only apply with PRB allocation in one of the component carriers. Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform.

# 6.4A.2.1.1 Error Vector magnitude for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

# 6.4A.2.1.1.1 Test Purpose

For 2UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in section 6.4.2.1.

# 6.4A.2.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

# 6.4A.2.1.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

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# 6.4A.2.1.1.4 Test description

# 6.4A.2.1.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR CA configuration specified in Table 5.5A. All of these configurations shall be tested with applicable test parameters for each CA configuration, are shown in Table 6.4A.2.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.2.1.1.4.1-1: Test Configuration Table for 2UL CA

# FFS

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals for PCC are initially set up according to Annex C.0, C.1 and C.3, and uplink signals according to Annex G.0, G.1 and G.3.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.1.1.4.3

# 6.4A.2.1.1.4.2 Test procedure

- 1. Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2. Configure SCC according to Annex C.0, C.1, C.3 for all downlink physical channels.
- 3. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.4A.2.1.1.4.3.
- 4. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [TBD], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause9.2).
- 5. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.1.1.4.1-1. Since the UE has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 6. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- Send continuously uplink power control "up" commands in the uplink scheduling information to the UE until the UE transmits at P<sub>UMAX</sub> level. Allow at least 200ms starting from the first TPC command in this step for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 8. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 9. Measure the  $EVM_{\theta}$ ,  $EVM_{\phi}$ ,  $EVM_{DMRS,\theta}$  and  $EVM_{DMRS,\phi}$  on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarizations, respectively. For TDD, only slots consisting of only UL symbols are under test. Calculate  $\overline{EVM}_{DMRS} = \min(\overline{EVM}_{DMRS,\theta}, \overline{EVM}_{DMRS,\phi})$  and  $EVM = \min(EVM_{\theta}, EVM_{\phi})$ .

- 10. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4A.2.1.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.
- NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

# Table 6.4A.2.1.1.4.2-1: Void

### Table 6.4A.2.1.1.4.2-2: Void

# Table 6.4A.2.1.1.4.2-3: Power Window (dB) for EVM PUSCH

FFS

6.4A.2.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.4A.2.1.1.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.1.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.1.5-1 when embedded with data symbols of the respective modulation scheme.

#### Table 6.4A.2.1.1.5-1: Test requirements for Error Vector Magnitude for CA

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.1.2 Error Vector magnitude for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.

# 6.4A.2.1.2.1 Test Purpose

For 3UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in clause 6.4.2.1.

# 6.4A.2.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

# 6.4A.2.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

# 6.4A.2.1.2.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1  $\rightarrow$  use Table 6.4A.2.1.2.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.2.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.2.5-1.

# Table 6.4A.2.1.2.4.1-1: Test Configuration Table for 3UL CA

FFS

# 6.4A.2.1.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4A.2.1.2.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.2.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.2.5-1 when embedded with data symbols of the respective modulation scheme.

#### Table 6.4A.2.1.2.5-1: Test requirements for Error Vector Magnitude

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

#### Table 6.4A.2.1.2.5-2: Test Tolerance for Error Vector Magnitude for CA

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.1.3 Error Vector magnitude for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.

# 6.4A.2.1.3.1 Test Purpose

For 4UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in clause 6.4.2.1.

# 6.4A.2.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.4A.2.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

# 6.4A.2.1.3.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1  $\rightarrow$  use Table 6.4A.2.1.3.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.3.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.3.5-1.

# Table 6.4A.2.1.3.4.1-1: Test Configuration Table for 4UL CA

#### FFS

6.4A.2.1.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.4A.2.1.3.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.3.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.3.5-1 when embedded with data symbols of the respective modulation scheme.

# Table 6.4A.2.1.3.5-1: Test requirements for Error Vector Magnitude

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

# Table 6.4A.2.1.3.5-2: Test Tolerance for Error Vector Magnitude for CA

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.1.4 Error Vector magnitude for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.

### 6.4A.2.1.4.1 Test Purpose

For 5UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in clause 6.4.2.1.

#### 6.4A.2.1.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

6.4A.2.1.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

6.4A.2.1.4.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1  $\rightarrow$  use Table 6.4A.2.1.4.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.4.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.4.5-1.

# Table 6.4A.2.1.4.4.1-1: Test Configuration Table for 5UL CA

FFS

6.4A.2.1.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.4A.2.1.4.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.4.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.4.5-1 when embedded with data symbols of the respective modulation scheme.

# Table 6.4A.2.1.4.5-1: Test requirements for Error Vector Magnitude for CA

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

6.4A.2.1.5 Error Vector magnitude for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.

# - Test configuration table is FFS.

# 6.4A.2.1.5.1 Test Purpose

For 6UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in clause 6.4.2.1.

# 6.4A.2.1.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

# 6.4A.2.1.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

# 6.4A.2.1.5.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1  $\rightarrow$  use Table 6.4A.2.1.5.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.5.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.5.5-1.

# Table 6.4A.2.1.5.4.1-1: Test Configuration Table for 6UL CA

#### FFS

## 6.4A.2.1.5.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4A.2.1.5.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.5.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.5.5-1 when embedded with data symbols of the respective modulation scheme.

# Table 6.4A.2.1.5.5-1: Test requirements for Error Vector Magnitude for CA

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

## Table 6.4A.2.1.5.5-2: Test Tolerance for Error Vector Magnitude for CA

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.1.6 Error Vector magnitude for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.

# 6.4A.2.1.6.1 Test Purpose

For 7UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in sub-section 6.4.2.1.

#### 6.4A.2.1.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.4A.2.1.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

#### 6.4A.2.1.6.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1 → use Table 6.4A.2.1.6.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.6.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.6.5-1.

# Table 6.4A.2.1.6.4.1-1: Test Configuration Table for 7UL CA

# FFS

6.4A.2.1.6.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.4A.2.1.6.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.6.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.6.5-1 when embedded with data symbols of the respective modulation scheme.

# Table 6.4A.2.1.6.5-1: Test requirements for Error Vector Magnitude for CA

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

## Table 6.4A.2.1.6.5-2: Test Tolerance for Error Vector Magnitude for CA

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.1.7 Error Vector magnitude for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty and Test Tolerance are FFS.
- Test configuration table is FFS.

# 6.4A.2.1.7.1 Test Purpose

For 8UL carrier aggregation, the Error Vector Magnitude requirement should be defined for each component carrier. Requirement applies for the allocated component carrier, when all other component carriers are activated, but not allocated.

Similar transmitter impairment removal procedures are applied for CA waveform before EVM calculation as is specified for non-CA waveform in sub-section 6.4.2.1.

## 6.4A.2.1.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

#### 6.4A.2.1.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.1.0

# 6.4A.2.1.7.4 Test description

Same as in clause 6.4A.2.1.1.4 with following exceptions:

- Instead of Table 6.4A.2.1.1.4.1-1  $\rightarrow$  use Table 6.4A.2.1.7.4.1-1.
- Instead of clause 6.4A.2.1.1.4.3  $\rightarrow$  use clause 6.4A.2.1.7.4.3.
- Instead of Table 6.4A.2.1.1.5-1  $\rightarrow$  use Table 6.4A.2.1.7.5-1.

# Table 6.4A.2.1.7.4.1-1: Test Configuration Table for 8UL CA

FFS

# 6.4A.2.1.7.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4A.2.1.7.5 Test requirement

The PUSCH EVM, derived in Annex E.4.2, shall not exceed the values in Table 6.4A.2.1.7.5-1.

The PUSCH  $EVM_{DMRS}$ , derived in Annex E.4.6.2, shall not exceed the values in Table 6.4A.2.1.7.5-1 when embedded with data symbols of the respective modulation scheme.

Parameter	Unit	Average EVM Level	Reference Signal EVM Level
Pi/2 BPSK	%	30+TT	30+TT
QPSK	%	17.5+TT	17.5+TT
16 QAM	%	12.5+TT	12.5+TT
64 QAM	%	8+TT	8+TT

#### Table 6.4A.2.1.7.5-1: Test requirements for Error Vector Magnitude for CA

# Table 6.4A.2.1.7.5-2: Test Tolerance for Error Vector Magnitude for CA

Test Metric	FR2a	FR2b
Quiet Zone size ≤ 30 cm	FFS	FFS

# 6.4A.2.2 Carrier leakage for CA

# 6.4A.2.2.0 Minimum conformance requirements

#### 6.4A.2.2.0.1 General

Carrier leakage is an additive sinusoid waveform. The carrier leakage requirement is defined for each component carrier and is measured on the component carrier with PRBs allocated. The measurement interval is one slot in the time domain.

Note: When UE has DL configured for non-contiguous CA, carrier leakage may land outside the spectrum occupied by all configured UL and DL CC.

The relative carrier leakage power is a power ratio of the additive sinusoid waveform and the modulated waveform. The requirement is verified with the test metric of Carrier Leakage (Link=TX beam peak direction, Meas=Link angle).

# 6.4A.2.2.0.2 Carrier leakage for power class 1

When carrier leakage is contained inside the spectrum occupied by all configured UL and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4A.2.2.0.2-1 for power class 1 UEs.

#### Table 6.4A.2.2.0.2-1: Minimum requirements for relative carrier leakage for power class 1

Parameters	Relative Limit (dBc)
EIRP > 17 dBm	-25
4 dBm ≤ EIRP ≤ 17 dBm	-20

6.4A.2.2.0.3 Carrier leakage for power class 2

When carrier leakage is contained inside the spectrum occupied by all configured UL and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4A.2.2.0.3-1 for power class 2.

### Table 6.4A.2.2.0.3-1: Minimum requirements for relative carrier leakage power class 2

Parameters	Relative limit (dBc)
EIRP > 6 dBm	-25
-13 dBm ≤ EIRP ≤ 6 dBm	-20

6.4A.2.2.0.4 Carrier leakage for power class 3

When carrier leakage is contained inside the spectrum occupied by all configured UL and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4A.2.2.0.4-1 for power class 3 UEs.

#### Table 6.4A.2.2.0.4-1: Minimum requirements for relative carrier leakage power class 3

Parameters	Relative limit (dBc)
Output power > 0 dBm	-25
-13 dBm ≤ Output	-20
power EIRP ≤ 0 dBm	-20

# 6.4A.2.2.0.5 Carrier leakage for power class 4

When carrier leakage is contained inside the spectrum occupied by all configured UL and DL CCs, the relative carrier leakage power shall not exceed the values specified in Table 6.4A.2.2.0.5-1 for power class 4 UEs.

#### Table 6.4A.2.2.0.5-1: Minimum requirements for relative carrier leakage power class 4

Parameters	Relative limit (dBc)
Output power > 11 dBm	-25
-13 dBm ≤ Output power EIRP ≤ 11 dBm	-20

# 6.4A.2.2.1 Carrier leakage for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

#### 6.4A.2.2.1.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

# 6.4A.2.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

#### 6.4A.2.2.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

#### 6.4A.2.2.1.4 Test description

### 6.4A.2.2.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

			Defau	ult Conditi	ons	
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]			Normal			
Test Frequencies as specified in TS 38.508-1 [10]			Low and High range			
	subclause [4.3.1.2.3] for different CA bandwidth					
classes						
Test CC Combination setting (aggregated BW of the			Lowest aggregated BW			
	guration) as specified					
the CA C	onfiguration across b	andwidth con	nbination			
sets sup	ported by the UE					
Test SCS	S as specified in Table	9 5.3.5-1		Lowest		
				t Paramete		
CA Co	onfiguration / Aggreg	jated BW		nlink	Uplink Configuration	
				uration		
Test	CC & Mapping	CBW	RB allocation		Modulation	RB allocation
ID	(NOTE 5)	(MHz)				(NOTE 1)
	PCC/CC1	50	N/A for this test		DFT-s-OFDM	Inner_4RB_Left for PC2, PC3,
4					QPSK	PC4
1						Inner_16RB_Left_Region2 for PC1
	SCC/CC2	50	4			FGI
NOTE 1			h RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table			
6.1-2 for			ITINI alloca			
	-	est cumulativ	e andredate	ed BW setti	ngs are checked se	enarately for each CA
NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.						
NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated						
BW, only the combination with the lowest PCC ChBW is tested.						
NOTE 4: When the signalled DC carrier position is at Inner_4RB_Left for PC2, PC3, PC4, use Inner_4RB_Right for						
UL RB allocation. When the signalled DC carrier position is in Inner_16RB_Left_Region2 for PC1, use						
	Inner_16RB_Right_Region2 for UL RB allocation.					
NOTE 5:						C is on component carrier CCj,
with CCi or CCj frequencies defined in TS38.508-1 [10].						
	with CCi or CCj free	uencies defir	ned in TS38	3.508-1 [10]		

# Table 6.4A.2.2.1.4.1-1: Intra-band Contiguous CA Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.1.4.3

# 6.4A.2.2.1.4.2 Test procedure

- 1. Configure PCC and SCC according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.1.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.

- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4A.2.2.1.4.2-1 according to the power class.  $P_W$  is the power window according to Table [TBD] for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

Table 6.4A.2.2.1.4.2-1: UE EIRP Preq (dBm) for carrier leakage

# Table 6.4A.2.2.1.4.2-2: Power Window (dB) for carrier leakage

FFS

# 6.4A.2.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4A.2.2.1.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

CarrLeak<sub>Total</sub> = 
$$10 \log_{10} \left( 10^{\text{CarrLeak}_{\theta}/10} + 10^{\text{CarrLeak}_{\phi}/10} \right)$$
, where  

$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1 table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

# 6.4A.2.2.2 Carrier leakage for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

### 6.4A.2.2.2.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

# 6.4A.2.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.4A.2.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

# 6.4A.2.2.2.4 Test description

# 6.4A.2.2.2.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.2.2.2.4.1-1: Intra-band Contiguous CA Test Configuration Table

Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]			Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes			Low and High range			
Test CC Combination setting (aggregated BW of the CA configuration) as specified in Table 5.5A.1-1 for the CA Configuration across bandwidth combination sets supported by the UE			Lowest aggregated BW			
Test SCS	Test SCS as specified in Table 5.3.5-1			Lowest		
	Test			t Paramete	ers	
		nlink uration	Uplink Configuration			
Test ID	CC & Mapping (NOTE 5)	CBW (MHz)	RB allocation		Modulation	RB allocation (NOTE 1)
1	PCC/CC1	50	N/A for this test		DFT-s-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1
	SCC/CC2	50	ļ			
	SCC/CC3	50				

NOTE 1: The specific configuration of each RF allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.

NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.

NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated BW, only the combination with the lowest PCC ChBW is tested.

NOTE 4: When the signalled DC carrier position is at Inner\_4RB\_Left for PC2, PC3, PC4, use Inner\_4RB\_Right for UL RB allocation. When the signalled DC carrier position is in Inner\_16RB\_Left\_Region2 for PC1, use Inner\_16RB\_Right\_Region2 for UL RB allocation.

NOTE 5: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj, with CCi or CCj frequencies defined in TS38.508-1 [10].

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.2.4.3

# 6.4A.2.2.2.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.2.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.2.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4A.2.2.2.4.2-1 according to the power class.  $P_W$  is the power window according to Table [TBD] for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

# Table 6.4A.2.2.2.4.2-2: Power Window (dB) for carrier leakage

# TBD

# 6.4A.2.2.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4A.2.2.2.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

$$\operatorname{CarrLeak}_{\operatorname{Total}} = 10 \log_{10} \left( 10^{\operatorname{CarrLeak}_{\theta}/10} + 10^{\operatorname{CarrLeak}_{\phi}/10} \right), \text{ where}$$
$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}.$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

# 6.4A.2.2.3 Carrier leakage for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

# 6.4A.2.2.3.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

#### 6.4A.2.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

# 6.4A.2.2.3.3 Minimum conformance requirements

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4A.2.2.

# 6.4A.2.2.3.4 Test description

# 6.4A.2.2.3.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.2.2.3.4.1-1: Intra-band Contiguous CA Test Configuration Table

			Defa	ult Conditi	ons			
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]			Normal					
Test Frequencies as specified in TS 38.508-1 [10]			Low and	Low and High range				
	subclause [4.3.1.2.3] for different CA bandwidth							
	and PCC and SCC ar							
	frequencies according Combination setting (			Lowester	Louis et a nom meta el DIM			
	guration) as specified			Lowesta	Lowest aggregated BW			
	Configuration across b							
	ported by the UE							
	S as specified in Table	e 5.3.5-1		Lowest				
	•		Tes	t Paramete				
CA Co	onfiguration / Aggreg	jated BW		nlink	Up	link Configuration		
	•			uration		1		
Test	CC & Mapping	CBW	RB allocation		Modulation	RB allocation		
ID	(NOTE 5) PCC/CC1	(MHz)				(NOTE 1)		
		50	N/A for this test		DFT-s-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4		
					QFON	Inner_16RB_Left_Region2 for		
						PC1		
	SCC/CC2	50			DFT-s-OFDM			
1					QPSK			
	SCC/CC3	50			DFT-s-OFDM			
					QPSK			
	SCC/CC4	50			DFT-s-OFDM			
NOTE 4	·c			·· · · · ·	QPSK			
		iration of eac	h RF alloca	tion is defir	ned in Table 6.1-1 f	or PC2, PC3 and PC4 or Table		
6.1-2 for PC1.								
NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.								
NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated								
BW, only the combination with the lowest PCC ChBW is tested.								
NOTE 4:	NOTE 4: When the signalled DC carrier position is at Inner_4RB_Left for PC2, PC3, PC4, use Inner_4RB_Right for							
	UL RB allocation. When the signalled DC carrier position is in Inner_16RB_Left_Region2 for PC1, use							
	Inner_16RB_Right_Region2 for UL RB allocation.							
NOTE 5: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj,								
with CCi or CCj frequencies defined in TS38.508-1 [10].								

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.

- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.3.4.3

# 6.4A.2.2.3.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.3.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Tables 6.4A.2.2.3.4.2-1 according to the power class.  $P_W$  is the power window according to Table [TBD] for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

Table 6.4A.2.2.3.4.2-1: UE EIRP Preq (dBm) for carrier leakage

# Table 6.4A.2.2.3.4.2-2: Power Window (dB) for carrier leakage

FFS

#### 6.4A.2.2.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

## 6.4A.2.2.3.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

CarrLeak<sub>Total</sub> = 
$$10 \log_{10} \left( 10^{\text{CarrLeak}_{\theta}/10} + 10^{\text{CarrLeak}_{\phi}/10} \right)$$
, where  

$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

# 6.4A.2.2.4 Carrier leakage for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.

# 6.4A.2.2.4.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

#### 6.4A.2.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

6.4A.2.2.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

- 6.4A.2.2.4.4 Test description
- 6.4A.2.2.4.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.4.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

			Def	ault Condit	ions		
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]				Normal			
Test Frequencies as specified in TS 38.508-1 [10]				Low and H	ligh range		
	se [4.3.1.2.3] for diffe						
	and PCC and SCCs						
	frequencies accordin						
	Combination setting			Lowest ag	gregated BW		
	configuration) as species						
	tion sets supported b		1				
	S as specified in Tab			Lowest			
1631 00		ne 0.0.0-1	Te	st Paramet	ers		
CA Co	nfiguration / Aggre	gated BW		nlink		link Configuration	
	J			uration			
Test ID	CC & Mapping (NOTE 5)	CBW (MHz)	RB all	ocation	Modulation	RB allocation (NOTE 1)	
	PCC/CC1	50			DFT-s-OFDM	Inner_4RB_Left for PC2, PC3,	
			N/A for this test		QPSK	PC4	
			N/A IO	lins lest		Inner_16RB_Left_Region2 for PC1	
	SCC/CC2	50			-	-	
1	SCC/CC3	50			-	-	
	SCC/CC4	50			-	-	
	SCC/CC5	50			-	-	
6.1-2 for	PC1. CA Configuration	Test cumulati	ive aggrega	ated BW set	tings are checked s	for PC2, PC3 and PC4 or Table eparately for each CA ified in Table 5.5A.1-1.	
NOTE 3		multiple CC (	Combinatio	ns in the CA	A Configuration with	the same cumulative aggregated	
NOTE 4	When the signalle	d DC carrier	position is a	at Inner_4R	B_Left for PC2, PC	3, PC4, use Inner_4RB_Right for 3_Left_Region2 for PC1, use	
	Inner_16RB_Right						
NOTE 5		C/CCj means	PCC is on	component		C is on component carrier CCj,	
		equencies de		30.300-111	UI.		

# Table 6.4A.2.2.4.4.1-1: Intra-band Contiguous CA Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.4.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.4.4.3

### 6.4A.2.2.4.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.4.4.3.

- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.4.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Table 6.4A.2.2.4.4.2-1 according to the power class. P<sub>W</sub> is the power window according to Table 6.4A.2.2.4.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### Table 6.4A.2.2.4.4.2-1: UE EIRP Preq (dBm) for carrier leakage

Power Class	Preq (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

#### Table 6.4A.2.2.4.4.2-2: Power Window (dB) for carrier leakage

TBD

#### 6.4A.2.2.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4A.2.2.4.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

$$\operatorname{CarrLeak}_{\operatorname{Total}} = 10 \log_{10} \left( 10^{\operatorname{CarrLeak}_{0}/10} + 10^{\operatorname{CarrLeak}_{0}/10} \right), \text{ where}$$
$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}.$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

# 6.4A.2.2.5 Carrier leakage for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.

#### 6.4A.2.2.5.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

## 6.4A.2.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.4A.2.2.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

- 6.4A.2.2.5.4 Test description
- 6.4A.2.2.5.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.5.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

## Table 6.4A.2.2.5.4.1-1: Intra-band Contiguous CA Test Configuration Table

			Def	ault Condi	tions		
Test Environment as specified in TS 38.508-1 [10] subclause [4.1]				Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2					High range		
Test CC Combination setting (aggregated BW of the CA configuration) as specified in Table 5.5A.1- 1 for the CA Configuration across bandwidth combination sets supported by the UE				Lowest aggregated BW			
Test SC	S as specified in Tab	ole 5.3.5-1	Та	Lowest	Lowest		
CA Co	CA Configuration / Aggregated BW Dow			nlink uration	link Uplink Configuration		
Test ID	CC & Mapping (NOTE 5)	CBW (MHz)		ocation	Modulation	RB allocation (NOTE 1)	
	PCC/CC1	50	N/A for	this test	DFT-s-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1	
	SCC/CC2	50			-	-	
1	SCC/CC3	50			-	-	
	SCC/CC4	50			-	-	
	SCC/CC5	50			-	-	

	SCC/CC6	50		-	-			
NOTE 1	The specific confi	nuration of ea	ach RB allocation is def	ined in Table 6 1-1	for PC2, PC3 and PC4 or Table			
NOTE 1.	6.1-2 for PC1.	guiation of ce						
NOTE 2			ive aggregated BW set					
NOTE					cified in Table 5.5A.1-1.			
NOTE 3	NOTE 3: If the UE supports multiple CC Combinations in the CA Configuration with the same cumulative aggregated BW, only the combination with the lowest PCC ChBW is tested.							
NOTE 4					C3, PC4, use Inner_4RB_Right for			
	UL RB allocation.	When the sig	nalled DC carrier posit		B_Left_Region2 for PC1, use			
			r UL RB allocation.					
NOTE 5					C is on component carrier CCj,			
	with CCi or CCi fre	equencies de	fined in TS 38.508-1 [1	0].				

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.5.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.5.4.3

#### 6.4A.2.2.5.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.5.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.5.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Table 6.4A.2.2.5.4.2-1 according to the power class.  $P_W$  is the power window according to Table 6.4A.2.2.5.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

#### Table 6.4A.2.2.5.4.2-1: UE EIRP Preq (dBm) for carrier leakage

#### Table 6.4A.2.2.5.4.2-2: Power Window (dB) for carrier leakage

TBD

#### 6.4A.2.2.5.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4A.2.2.5.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

$$\operatorname{CarrLeak}_{\text{Total}} = 10 \log_{10} \left( 10^{\operatorname{CarrLeak}_{\theta}/10} + 10^{\operatorname{CarrLeak}_{\phi}/10} \right), \text{ where}$$
$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

## 6.4A.2.2.6 Carrier leakage for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.

## 6.4A.2.2.6.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

#### 6.4A.2.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.4A.2.2.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

## 6.4A.2.2.6.4 Test description

## 6.4A.2.2.6.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.6.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.2.2.6.4.1-1: Intra-band Contiguous CA Test Configuration Table

				ault Condi	tions			
Test Env subclaus	vironment as specifie	d in TS 38.5	08-1 [10]	Normal				
Test Fre subclaus classes,	quencies as specifie se [4.3.1.2.3] for diffe and PCC and SCCs	rent CA ban are mapped	dwidth I onto	Low and High range				
physical frequencies according to Table 6.1-2 Test CC Combination setting (aggregated BW of the CA configuration) as specified in Table 5.5A.1- 1 for the CA Configuration across bandwidth combination sets supported by the UE				Lowest aggregated BW				
Test SC	S as specified in Tab	le 5.3.5-1		Lowest				
	<i></i>			st Parame				
	nfiguration / Aggree	_	Config	nlink uration	-	link Configuration		
Test ID	CC & Mapping (NOTE 5)	CBW (MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)		
	PCC/CC1	50	N/A for	this test	DFT-s-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
	SCC/CC2	50			-	-		
	SCC/CC3	50			-	-		
1	SCC/CC4	50			-	-		
	SCC/CC5	50			-	-		
	SCC/CC6	50			-	-		
	SCC/CC7	50			-	-		
	6.1-2 for PC1.					for PC2, PC3 and PC4 or Table		
	NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1.							
	BW, only the comb	ination with	the lowest F	PCC ChBW	is tested.	the same cumulative aggregated		
NOTE 4	: When the signalle UL RB allocation.	d DC carrier When the sig	position is a gnalled DC	at Inner_4R carrier posit	B_Left for PC2, PC	3, PC4, use Inner_4RB_Right for 3_Left_Region2 for PC1, use		
NOTE 5	Inner_16RB_Right_Region2 for UL RB allocation. NOTE 5: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj, with CCi or CCj frequencies defined in TS 38.508-1 [10].							

1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.

2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.

- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.6.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.6.4.3

### 6.4A.2.2.6.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.6.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.6.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Table 6.4A.2.2.6.4.2-1 according to the power class. P<sub>W</sub> is the power window according to Table 6.4A.2.2.6.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	P <sub>req</sub> (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

#### Table 6.4A.2.2.6.4.2-1: UE EIRP Preq (dBm) for carrier leakage

#### Table 6.4A.2.2.6.4.2-2: Power Window (dB) for carrier leakage

FFS

#### 6.4A.2.2.6.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 6.4A.2.2.6.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

CarrLeak<sub>Total</sub> = 
$$10 \log_{10} \left( 10^{\text{CarrLeak}_{\theta}/10} + 10^{\text{CarrLeak}_{\phi}/10} \right)$$
, where  
 $n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$ .

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

# 6.4A.2.2.7 Carrier leakage for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Test procedure is incomplete due to power window is TBD
- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA is TBD.

## 6.4A.2.2.7.1 Test purpose

Carrier leakage expresses itself as unmodulated sine wave with the carrier frequency. It is an interference of approximately constant amplitude and independent of the amplitude of the wanted signal. Carrier leakage interferes with the sub carriers at its position (if allocated), especially, when their amplitude is small.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of carrier leakage.

#### 6.4A.2.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

6.4A.2.2.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.2.0.

- 6.4A.2.2.7.4 Test description
- 6.4A.2.2.7.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA configuration and subcarrier spacing, are shown in table 6.4A.2.2.7.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

			Def	ault Condi	ions			
Test Env subclaus	vironment as specifie se [4.1]	d in TS 38.5		Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto				Low and High range				
	frequencies accordin				( 1014)			
	Combination setting configuration) as spe			Lowest ag	gregated BW			
	CA Configuration ac							
combina	tion sets supported b	by the UE						
Test SC	S as specified in Tab	le 5.3.5-1		Lowest				
				st Parame				
CACO	nfiguration / Aggree	gated BW	-	nlink uration	Up	link Configuration		
Test ID	CC & Mapping (NOTE 5)	CBW (MHz)		ocation	Modulation	RB allocation (NOTE 1)		
	PCC/CC1	50	N/A for	this test	DFT-s-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
	SCC/CC2	50			-	-		
	SCC/CC3	50			-	-		
1	SCC/CC4	50			-	-		
	SCC/CC5	50			-	-		
	SCC/CC6	50			-	-		
	SCC/CC7	50			-	-		
	SCC/CC8	50			-	-		
		guration of ea	ach RB allo	cation is def	ined in Table 6.1-1	for PC2, PC3 and PC4 or Table		
6.1-2 for		Toot ourselft		tod DW/	tingo oro checker	energialy for each CA		
NOTE 2						eparately for each CA cified in Table 5.5A.1-1.		
NOTE 3		multiple CC	Combinatio	ns in the C/	A Configuration with	the same cumulative aggregated		
	: When the signalle	d DC carrier When the sig t_Region2 fo	position is a malled DC o r UL RB alle	at Inner_4R carrier posit ocation.	B_Left for PC2, PC ion is in Inner_16RI	3, PC4, use Inner_4RB_Right for B_Left_Region2 for PC1, use		

# Table 6.4A.2.2.7.4.1-1: Intra-band Contiguous CA Test Configuration Table

NOTE 5: PCC/CCi and SCC/CCj means PCC is on component carrier CCi and SCC is on component carrier CCj, with CCi or CCj frequencies defined in TS 38.508-1 [10].

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.2.7.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.2.7.4.3

#### 6.4A.2.2.7.4.2 Test procedure

- 1. Configure PCC and SCCs according to Annex C.0, C.1, C.2 and Annex C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCCs as per TS 38.508-1 [10] clause 5.5.1 Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.2.7.4.3.
- 3. SS activates SCCs by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.2.7.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 6. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 5. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE EIRP is in the range  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Table 6.4A.2.2.7.4.2-1 according to the power class.  $P_W$  is the power window according to Table 6.4A.2.2.7.4.2-2 for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 8. Measure carrier leakage on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ -polarization. For TDD, only slots consisting of only UL symbols are under test.
- 9. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Power Class	Preq (dBm) for step 5
Power Class 1	17
Power Class 2	6
Power Class 3	0
Power Class 4	11

#### Table 6.4A.2.2.7.4.2-1: UE EIRP Preq (dBm) for carrier leakage

#### Table 6.4A.2.2.7.4.2-2: Power Window (dB) for carrier leakage

FFS

#### 6.4A.2.2.7.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.4A.2.2.7.5 Test requirement

For each of the *n* carrier leakage results derived in Annex E.3.1 for  $\theta$ - and  $\varphi$ -polarization the total value is calculated according to

$$\operatorname{CarrLeak}_{\operatorname{Total}} = 10 \log_{10} \left( 10^{\operatorname{CarrLeak}_{\theta}/10} + 10^{\operatorname{CarrLeak}_{\phi}/10} \right), \text{ where}$$
$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}.$$

Each of the *n* total carrier leakage results CarrLeak<sub>Total</sub> shall not exceed the values in table 6.4.2.2.5-1 for power class 1, table 6.4.2.2.5-2 for power class 2, table 6.4.2.2.5-3 for power class 3 and table 6.4.2.2.5-4 for power class 4. Allocated RBs are not under test.

6.4A.2.3 In-band emissions for CA

#### 6.4A.2.3.0 Minimum conformance requirements

6.4A.2.3.0.1 General

Inband emission requirement is defined over the spectrum occupied by all configured UL and DL CCs. The measurement interval is as defined in section 6.4.2.4. The requirement is verified with the test metric of In-band emission (Link=TX beam peak direction, Meas=Link angle).

For intra-band contiguous carrier aggregation, the requirements in this clause apply with all component carriers active and with one single contiguous PRB allocation in one of uplink component carriers. The inband emission is defined as the interference falling into the non-allocated resource blocks for all component carriers.

6.4A.2.3.0.2 In-band emissions for power class 1

The relative in-band emission shall not exceed the values specified in Table 6.4A.2.3.0.2-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General	dB	n	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image	dB	-25	Output power > 27 dBm	Image frequencies
i w illiage	uВ	-20	Output power ≤ 27 dBm	(NOTES 2, 3)
Carrier	dBc	-25	Output power > 17 dBm	Carrier frequency
leakage		-20	4 dBm ≤ Output power ≤ 17 dBm limit is evaluated in each non-allocated RB. For each such I	(NOTES 4, 5)
NOTE 2: The RB RB/2 the NOTE 3: Ima NOTE 4: The RB NOTE 4: The RB NOTE 5: The the NOTE 6: $L_{CR}$ NOTE 6: $L_{CR}$ NOTE 7: EV NOTE 8: $\Delta_{RE}$ car NOTE 9: $P_{RE}$	rrier lease mease to the 2 BPSK 2 BP	akage) that apply. <i>P<sub>RB</sub></i> is urement bandwidth is 1 measured average pow ( with Spectrum Shapin ured power in the alloca quencies for UL CA are urement bandwidth is 1 measured total power i cable frequencies for th Bs immediately adjacer a Transmission Bandwid limit for the modulation starting frequency offse or the first adjacent RB acing between the CCs	RB and the limit is expressed as a ratio of measured power wer per allocated RB, where the averaging is done across a lig, the limit is expressed as a ratio of measured power in or ted RB with highest PSD. specified in relation to either UL or DL carrier frequency. RB and the limit is expressed as a ratio of measured power n all allocated RBs. is limit are those that are enclosed in the RBs containing the to the DC frequency but excluding any allocated RB. dth for kth allocated component carrier (see Figure 5.3.3-1) n format used in the allocated RBs. et between the allocated RB and the measured non-allocate outside of the allocated bandwidth), and may take non-inter is not a multiple of RB. allocated RB, measured in dBm.	er in one non-allocated Il allocated RBs. For ne non-allocated RB to er in one non-allocated e DC frequency, or in ed RB (e.g. $\Delta_{RB} = 1$ or

#### 6.4A.2.3.0.3 In-band emissions for power class 2

The relative in-band emission shall not exceed the values specified in Table 6.4A.2.3.0.3-1 for power class 2.

Paramete descriptio	- Unit		Limit (NOTE 1)	Applicable Frequencies			
General	dB		$max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10}(EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix}$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)			
IQ Image	e dB	-25	Output power > 16 dBm	Image frequencies			
		-20	Output power ≤ 16 dBm	(NOTES 2, 3)			
Carrier	dBc	-25	Output power > 6 dBm	Carrier frequency			
leakage		-20	-13 dBm ≤ Output power ≤ 6 dBm	(NOTES 4, 5)			
NOTE 1:			limit is evaluated in each non-allocated RB. For each such				
			higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values	(General, IQ Image or			
	Carrier lea	akage) that apply. P <sub>RB</sub>	is defined in NOTE 9.				
	RB to the Pi/2 BPSł the measu	measured average po ( with Spectrum Shapi ured power in the alloc	1 RB and the limit is expressed as a ratio of measured power wer per allocated RB, where the averaging is done across a ng, the limit is expressed as a ratio of measured power in or rated RB with highest PSD.	II allocated RBs. For			
			e specified in relation to either UL or DL carrier frequency.				
NOTE 4:			1 RB and the limit is expressed as a ratio of measured power	er in one non-allocated			
	RB to the measured total power in all allocated RBs. NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.						
			vidth for kth allocated component carrier (see Figure 5.3.3-1)				
			on format used in the allocated RBs.				
NOTE 8:			set between the allocated RB and the measured non-allocated				
			3 outside of the allocated bandwidth), and may take non-inte	ger values when the			
			s is not a multiple of RB.				
			allocated RB, measured in dBm.				
NOTE 10:	All powers	are EIRP in beam pe	ak direction.				

# Table 6.4A.2.3.0.3-1: Requirements for in-band emissions for power class 2

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### 6.4A.2.3.0.4 In-band emissions for power class 3

The relative in-band emission shall not exceed the values specified in Table 6.4A.2.3.0.4-1 for power class 3 UEs.

## Table 6.4A.2.3.0.4-1: Requirements for in-band emissions for power class 3

Parameter description	Unit		Applicable Frequencies	
General	dB		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image	dB	-25 -20	Output power > 10 dBm Output power ≤ 10 dBm	Image frequencies (NOTES 2, 3)
Carrier	dBc	-25	Output power > 0 dBm	Carrier frequency
leakage	ubc	-20	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRR</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM s the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	All powers are EIRP in beam peak direction.

#### 6.4A.2.3.0.5 In-band emissions for power class 4

The relative in-band emission shall not exceed the values specified in Table 6.4A.2.3.0.5-1 for power class 4 UEs.

Parameter description	Unit	Limit (NOTE 1)	Applicable Frequencies
General	dB	$max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10}(EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \end{bmatrix}$	Any non-allocated RB in allocated component carrier and not allocated
		$\begin{bmatrix} & -55.1dBm - P_{RB} \end{bmatrix}$	component carriers (NOTE 2)
IQ Image	dB	-25         Output power > 21 dBm           -20         Output power ≤ 21 dBm	Image frequencies (NOTES 2, 3)
Carrier leakage	dBc	$\begin{array}{c c} -25 & \text{Output power } > 11 \text{ dBm} \\ -20 & -13 \text{ dBm} \le \text{Output power} \le 11 \text{ dBm} \end{array}$	Carrier frequency (NOTES 4, 5)
NOTE 2: The RE pi/ note 3: Ime NOTE 3: Ime NOTE 4: The RE NOTE 5: The the NOTE 5: The the NOTE 6: $L_{CA}$ NOTE 7: EV NOTE 8: $\Delta_R$ NOTE 8: $\Delta_R$ NOTE 9: $P_R$	arrier lea e meas 3 to the 2 BPSK e measu age free e meas 3 to the e applic e two RI $_{RB}$ is the $_{B}$ is the $_{B}$ = -1 for rrier spa $_{B}$ is the	In t is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit value akage) that apply. $P_{RB}$ is defined in NOTE 9. Urement bandwidth is 1 RB and the limit is expressed as a ratio of measured power measured average power per allocated RB, where the averaging is done across (with Spectrum Shaping, the limit is expressed as a ratio of measured power in ured power in the allocated RB with highest PSD. quencies for UL CA are specified in relation to either UL or DL carrier frequency urement bandwidth is 1 RB and the limit is expressed as a ratio of measured power measured total power in all allocated RBs. cable frequencies for this limit are those that are enclosed in the RBs containing as immediately adjacent to the DC frequency but excluding any allocated RB. Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3 a) limit for the modulation format used in the allocated RBs. starting frequency offset between the allocated RB and the measured non-allo- or the first adjacent RB outside of the allocated bandwidth), and may take non-i acing between the CCs is not a multiple of RB. transmitted power per allocated RB, measured in dBm. as are EIRP in beam peak direction.	ower in one non-allocated s all allocated RBs. For one non-allocated RB to ower in one non-allocated the DC frequency, or in -1). cated RB (e.g. $\Delta_{RB} = 1$ or

# 6.4A.2.3.1 In-band emissions for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD

- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

## 6.4A.2.3.1.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

## 6.4A.2.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

### 6.4A.2.3.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

6.4A.2.3.1.4 Test description

## 6.4A.2.3.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and CC combinations based on NR operating bands specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.4A.2.3.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

# Table 6.4A.2.3.1.4.1-1: Test Configuration Table

	Default Conditions						
	Test Environment as specified in TS 38.508-1 [10] subclause 4.1						
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.				Low and	High range		
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.				Highest a		ne CA configuration he CA configuration	
Test SCS	S as specified in T	Fable 5.3.5-1.		Lowest			
	Test I				rs		
CA C	onfiguration / Ag	gregated BW		nlink uration	Up	plink Configuration	
Test ID	CC & Mapping	ChBw(MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)	
1	PCC	Default	N/A		DFT-s-OFDM PI/2 BPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1	
	SCC1				-	-	

2	PCC			DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1	
	SCC1			-	-	
3	PCC			CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1	
	SCC1			-	-	
4	PCC			CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1	
	SCC1			-	-	
NOTE 1:	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.					
NOTE 2:	NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals for PCC are initially set up according to Annex C.0, C.1 and C.3.0 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.4A.2.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4A.2.3.1.4.3

#### 6.4A.2.3.1.4.2 Test procedure

- 1. Retrieve the LO position from the parameter txDirectCurrentLocation in UplinkTxDirectCurrent IE.
- 2. Configure SCC according to Annex C.0, C.1 and C.3.0 for all downlink physical channels.
- 3. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Procedure to configure SCC(s) for NR RF CA testing. Message contents are defined in clause 6.4A.2.3.1.4.3.
- 4. SS activates SCC by sending the activation MAC CE (Refer TS 38.321, clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 5. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4A.2.3.1.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 6. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.
- 7. Send the appropriate TPC commands in the uplink scheduling information to the UE until UE output power is  $P_{req} + P_W \pm P_W$ , where  $P_{req}$  is the power level specified in Table 6.4A.2.3.1.4.2-1 according to the power class with power ID = 1.  $P_W$  is the power window according to Table [TBD] for the carrier frequency f and the channel bandwidth BW. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 2) for the UE Tx beam selection to complete.

- 8. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.
- 9. Measure In-band emission  $IE_{\theta}$ ,  $IE_{\phi}$  on PCC using Global In-Channel Tx-Test (Annex E) for the  $\theta$  and  $\phi$ polarizations, respectively. Measure power spectral density on the SCC. For TDD, only slots consisting of only UL symbols are under test. Calculate  $IE = IE_{\theta} + IE_{\phi}$ , where the calculation is based on linear power ratios.
- 10. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 11. Repeat steps 6 through 10 until In-band emissions have been measured for all power IDs in Table 6.4A.2.3.1.4.2-1.
- NOTE 1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.4A.2.3.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config without CP-OFDM condition. When switching to CP-OFDM waveform, send an NR RRCReconfiguration message with CP-OFDM condition.

NOTE 2: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### Table 6.4A.2.3.1.4.2-1: Parameters for In-band emissions

Power ID	Unit	Level for power class 1	Level for power class 2	Level for power class 3	Level for power class 4
1	dBm	27	16	10	21
2	dBm	17	6	0	11

## Table 6.4A.2.3.1.4.2-2: Power Window (dB) for In-band emissions

FFS

6.4A.2.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

### 6.4A.2.3.1.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.1.5-1 for power class 1 UEs.

### Table 6.4A.2.3.1.5-1: Test Requirements for in-band emissions for power class 1

Parameter description	Unit		Applicable Frequencies	
General	dB	$max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10} (\text{EVM}) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB}, \end{bmatrix} + \text{TT}$		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT -20+TT	Output power > 27 dBm Output power ≤ 27 dBm	Image frequencies (NOTES 2, 3)
Carrier	dBc	-25+TT	Output power > 17 dBm	Carrier frequency
leakage	abo	-20+TT	4 dBm ≤ Output power ≤ 17 dBm	(NOTES 4, 5)

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
NOTE 5:	
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM s the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.1.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General	dB	$max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10} (\text{EVM}) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + \text{TT}$		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 16 dBm	Image frequencies
la inage	uВ	-20+TT	Output power ≤ 16 dBm	(NOTES 2, 3)
Carrier	dBc	-25+TT	Output power > 6 dBm	Carrier frequency
leakage		-20+TT	-13 dBm ≤ Output power ≤ 6 dBm limit is evaluated in each non-allocated RB. For each such I	(NOTES 4, 5)
NOTE 2: The RB $Pi/2$ the NOTE 3: Ima NOTE 4: The RB NOTE 5: The NOTE 5: The NOTE 6: $L_{CF}$ NOTE 6: $L_{CF}$ NOTE 7: EV NOTE 8: $\Delta_{RI}$ $\Delta_{RI}$ Car NOTE 9: $P_{RI}$	rrier lease mease to the 2 BPSK 2 BPSK 2 mease 2 age free e mease to the e applic $B_{B}$ is the $M$ s the $B_{B}$ is the $B_$	akage) that apply. <i>P<sub>RB</sub></i> is urement bandwidth is 1 measured average pov ( with Spectrum Shapin ured power in the alloca quencies for UL CA are urement bandwidth is 1 measured total power i cable frequencies for th Bs immediately adjacer a Transmission Bandwid b limit for the modulation starting frequency offso or the first adjacent RB acing between the CCs	RB and the limit is expressed as a ratio of measured power ver per allocated RB, where the averaging is done across a lig, the limit is expressed as a ratio of measured power in or ted RB with highest PSD. specified in relation to either UL or DL carrier frequency. RB and the limit is expressed as a ratio of measured power n all allocated RBs. is limit are those that are enclosed in the RBs containing the to the DC frequency but excluding any allocated RB. dth for kth allocated component carrier (see Figure 5.3.3-1) n format used in the allocated RBs. et between the allocated RB and the measured non-allocate outside of the allocated bandwidth), and may take non-inter is not a multiple of RB. allocated RB, measured in dBm.	er in one non-allocated Il allocated RBs. For ne non-allocated RB to er in one non-allocated e DC frequency, or in ed RB (e.g. $\Delta_{RB} = 1$ or

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.1.5-3 for power class 3 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General	dB	$max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1dBm - P_{RB} \end{bmatrix} + TT$		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 10 dBm	Image frequencies
la inage	uв	-20+TT	Output power ≤ 10 dBm	(NOTES 2, 3)
Carrier	dBc	-25+TT	Output power > 0 dBm	Carrier frequency
leakage		-20+TT	-13 dBm ≤ Output power ≤ 0 dBm limit is evaluated in each non-allocated RB. For each such l	(NOTES 4, 5)
NOTE 2: Ca NOTE 2: The RB Pi/ NOTE 3: Ima NOTE 3: Ima NOTE 4: The RB NOTE 5: The NOTE 5: $L_{CI}$ NOTE 6: $L_{CI}$ NOTE 7: EV NOTE 8: $\Delta_{RI}$ $\Delta_{RI}$ NOTE 9: $P_{RI}$	rrier lea e meas b to the 2 BPSK e measu age free e meas b to the e applic e two RI $_{RB}$ is the $_{RB}$ is the $_{R}$ is the $_{R}$ = -1 for rrier spa $_{B}$ is the	akage) that apply. <i>P<sub>RB</sub></i> is urement bandwidth is 1 measured average pow (with Spectrum Shapin ured power in the alloca quencies for UL CA are urement bandwidth is 1 measured total power i cable frequencies for th Bs immediately adjacer a Transmission Bandwid b limit for the modulation starting frequency offse or the first adjacent RB acing between the CCs	RB and the limit is expressed as a ratio of measured power wer per allocated RB, where the averaging is done across a lig, the limit is expressed as a ratio of measured power in or ted RB with highest PSD. specified in relation to either UL or DL carrier frequency. RB and the limit is expressed as a ratio of measured power n all allocated RBs. is limit are those that are enclosed in the RBs containing the to the DC frequency but excluding any allocated RB. dth for kth allocated component carrier (see Figure 5.3.3-1) n format used in the allocated RBs. et between the allocated RB and the measured non-allocate outside of the allocated bandwidth), and may take non-inte is not a multiple of RB. allocated RB, measured in dBm.	er in one non-allocated Il allocated RBs. For ne non-allocated RB to er in one non-allocated e DC frequency, or in ed RB (e.g. $\Delta_{RB} = 1$ or

# Table 6.4A.2.3.1.5-3: Test Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.1.5-4 for power class 4 UEs.

Parameter description	Unit		Applicable Frequencies	
General	dB	m	$ax \begin{bmatrix} -25 - 10 \cdot \log_{10} \left(\frac{N_{RB}}{L_{CRB}}\right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix}, +TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT -20+TT	Output power > 21 dBm Output power ≤ 21 dBm	Image frequencies (NOTES 2, 3)
Carrier leakage	dBc	-25+TT -20+TT	Output power > 11 dBm -13 dBm ≤ Output power ≤ 11 dBm	Carrier frequency (NOTES 4, 5)

# Table 6.4A.2.3.1.5-4: Test Requirements for in-band emissions for power class 4

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRR</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM s the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	: All powers are EIRP in beam peak direction.

# 6.4A.2.3.2 In-band emissions for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

### 6.4A.2.3.2.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

# 6.4A.2.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

## 6.4A.2.3.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

## 6.4A.2.3.2.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.2.4.1-1.

			Defa	ult Conditi	ons		
Test Env subclaus		ified in TS 38.508		Normal			
Test Free subclaus classes,	quencies as spec se [4.3.1.2.3] for c and PCC and SC	ified in TS 38.508- lifferent CA bandw CS are mapped ou rding to Table 6.1-	ridth nto	Low and High range			
Test CC subclaus CA Conf supporte	combination sett se 5.5A.1-1, 5.5A	ing as specified in 2-1 and 5.5A.2-2 f pandwidth combine	for the		Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration		
1001001			Tes	t Paramete	ers		
CA Co	onfiguration / Ag	gregated BW	Dow	nlink uration		link Configuration	
Test ID	CC & Mapping	ChBw(MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)	
1	PCC				DFT-s-OFDM PI/2 BPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1	
	SCC1 SCC2				-	-	
2	PCC				DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1	
	SCC1			-	-	-	
	SCC2	Default	N	/A	-	-	
3	PCC	Delault			CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1	
	SCC1				-	-	
	SCC2				-	-	
4	PCC				CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1	
	SCC1 SCC2				-	-	
NOTE 1		nfiguration of eac	h RB alloc	ation is de	ined in Table 6 1-1	for PC2_PC3 and PC4 or Table	
<ul> <li>NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.</li> <li>NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1</li> </ul>							

# Table 6.4A.2.3.2.4.1-1: Test Configuration Table for 3UL CA

# 6.4A.2.3.2.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.2.5-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies
General	dB	max	$-25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right),$ $20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}},$ $-55.1 dBm - P_{RB}$	+TT	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 27 dBm		Image frequencies
Carrier		-20+TT -25+TT	Output power ≤ 27 dBm Output power > 17 dBm		(NOTES 2, 3)
leakage	dBc	-20+TT	$4 \text{ dBm} \le \text{Output power} \le 17 \text{ dBm}$		Carrier frequency (NOTES 4, 5)
NOTE 2: Th RE Pi/ the NOTE 3: Im NOTE 3: Im NOTE 4: Th RE NOTE 5: Th the NOTE 6: $L_C$ NOTE 6: $L_C$ NOTE 7: EV NOTE 8: $\Delta_R$ $\Delta_R$ ca	rrier lea e meass b to the 2 BPSF e meass age free e meass to the e applie two RI $_{RB}$ is the 'M is the $_{B}$ is the $_{B}$ = -1 for rrier spa	akage) that apply. $P_{RB}$ is urement bandwidth is 1 measured average pow K with Spectrum Shapin ured power in the alloca quencies for UL CA are urement bandwidth is 1 measured total power in cable frequencies for thi Bs immediately adjacen e Transmission Bandwid e limit for the modulation starting frequency offse or the first adjacent RB of acing between the CCs	RB and the limit is expressed as a rer per allocated RB, where the ave g, the limit is expressed as a ratio o ted RB with highest PSD. specified in relation to either UL or RB and the limit is expressed as a n all allocated RBs. s limit are those that are enclosed in t to the DC frequency but excluding th for kth allocated component carr n format used in the allocated RBs. t between the allocated RB and the putside of the allocated bandwidth), is not a multiple of RB.	ratio of measured power raging is done across a f measured power in or DL carrier frequency. ratio of measured power in the RBs containing the any allocated RB. ier (see Figure 5.3.3-1) measured non-allocated	er in one non-allocated II allocated RBs. For the non-allocated RB to er in one non-allocated the DC frequency, or in the RB (e.g. $\Delta_{RB} = 1$ or
			allocated RB, measured in dBm.		
	-	s are EIRP in beam pea			

# Table 6.4A.2.3.2.5-1: Test Requirements for in-band emissions for power class 1

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For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.2.5-2 for power class 2 UEs.

Parameter description	Unit		Applicable Frequencies			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT	Output power > 16 dBm	Image frequencies (NOTES 2, 3)		
Carrier	dBc	-25+TT	Output power > 6 dBm	Carrier frequency		
leakage	<b>3</b> 20	-20+TT	-13 dBm ≤ Output power ≤ 6 dBm	(NOTES 4, 5)		

Table 6.4A.2.3.2.5-2: Test Requirements for in-band emissions for power class 2

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated
	RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	: All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.2.5-3 for power class 3 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies
General	dB	max	$\max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	
IQ Image	dB	-25+TT -20+TT	Output power > 10 dBm	Image frequencies (NOTES 2, 3)
Carrier		-20+11 -25+TT	Output power ≤ 10 dBm Output power > 0 dBm	Carrier frequency
leakage	dBc	-20+TT	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> = 1 for the first adjacent RB outside of the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB.</li> <li>NOTE 9: P<sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.</li> <li>NOTE 10: All powers are EIRP in beam peak direction.</li> </ul>				

Table 6.4A.2.3.2.5-3: Test Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.2.5-4 for power class 4 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies
General	dB	max	$\max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix}, +TT$		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 21 dBm		Image frequencies
-	_	-20+TT	Output power ≤ 21 dBm		(NOTES 2, 3)
Carrier leakage	dBc	-25+TT -20+TT	Output power > 11 dBm -13 dBm < Output power < 11 dBn	n	Carrier frequency (NOTES 4 5)
leakage       cdbc       -20+TT       -13 dBm ≤ Output power ≤ 11 dBm       (NOTES 4, 5)         NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( <i>P<sub>RB</sub></i> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. <i>P<sub>RB</sub></i> is defined in NOTE 9.         NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.         NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.         NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.         NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.         NOTE 6: L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).         NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.         NOTE 8: Δ <sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ <sub>RB</sub> = 1 or					
c NOTE 9: F	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB. NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm. NOTE 10: All powers are EIRP in beam peak direction.				

## Table 6.4A.2.3.2.5-4: Test Requirements for in-band emissions for power class 4

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# 6.4A.2.3.3 In-band emissions for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

#### 6.4A.2.3.3.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

#### 6.4A.2.3.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

## 6.4A.2.3.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

# 6.4A.2.3.3.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.3.4.1-1.

## Table 6.4A.2.3.3.4.1-1: Test Configuration Table for 4UL CA

			Defa	ult Conditi	ons			
Test Env subclaus		cified in TS 38.508	-1 [10]	Normal	Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.				Low and High range				
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.					Lowest aggregated BW of the CA configuration Highest aggregated BW of the CA configuration			
	S as specified in	Table 5.3.5-1.		Lowest				
			Tes	t Paramete	ers			
CA Co	onfiguration / Ag	gregated BW		nlink uration	Up	link Configuration		
Test ID	CC & Mapping	ChBw(MHz)	RB all	ocation	Modulation	RB allocation (NOTE 1)		
1	PCC				DFT-s-OFDM PI/2 BPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
	SCC1				-	-		
	SCC2				-	-		
	SCC3				-	-		
2	PCC				DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1		
	SCC1				-	-		
	SCC2				-	-		
	SCC3	Default	N	/A	-	-		
3	PCC	Delault		/A	CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
•	SCC1				-	-		
	SCC2				-	-		
	SCC3				-	-		
4	PCC				CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1		
	SCC1				-	-		
	SCC2				-	-		
	SCC3							
NOTE 1:	6.1-2 for PC1.	0				1 for PC2, PC3 and PC4 or Table		
NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1								

## 6.4A.2.3.3.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.3.5-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies	
General	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{\mathbf{N}_{RB}}{\mathbf{L}_{CRB}} \right), \\ ( \Delta_{PB}  - 1) \end{bmatrix} + TT$		Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)			
IQ Image	dB	-25+TT	Output power > 27 dBm		Image frequencies	
		-20+TT	Output power ≤ 27 dBm		(NOTES 2, 3)	
Carrier leakage	dBc	-25+TT -20+TT	Output power > 17 dBm 4 dBm ≤ Output power ≤ 17 dBm		Carrier frequency (NOTES 4, 5)	
	in-han	-	imit is evaluated in each non-allocat	ed RB. For each such I		
NOTE 2: The Reprint of the second se	<ul> <li>requirement is calculated as the higher of (P<sub>RB</sub> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB.</li> </ul>					
	DTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.					
NOTE 10: Al	powers	s are EIRP in beam pea	k direction.			

# Table 6.4A.2.3.3.5-1: Test Requirements for in-band emissions for power class 1

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For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.3.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT	Output power > 16 dBm	Image frequencies		
		-20+TT	Output power ≤ 16 dBm	(NOTES 2, 3)		
Carrier	dBc	-25+TT	Output power > 6 dBm	Carrier frequency		
leakage	UBC	-20+TT	-13 dBm ≤ Output power ≤ 6 dBm	(NOTES 4, 5)		

Table 6.4A.2.3.3.5-2: Test Requirements for in-band emissions for power class 2

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	: All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.3.5-3 for power class 3 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies		
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT	Output power > 10 dBm	Image frequencies		
Carrier		-20+TT -25+TT	Output power ≤ 10 dBm Output power > 0 dBm	(NOTES 2, 3) Carrier frequency		
leakage	dBc	-20+TT	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)		
	n in-ban					
NOTE 2: The Replacement of the R	<ul> <li>RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB with highest PSD.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> </ul>					
NOTE 9: P <sub>F</sub>	carrier spacing between the CCs is not a multiple of RB. IOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.					
NOTE 10: All powers are EIRP in beam peak direction.						

Table 6.4A.2.3.3.5-3: Test Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.3.5-4 for power class 4 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies	
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix}$	+TT	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image	dB	-25+TT	Output power > 21 dBm		Image frequencies	
		-20+TT	Output power ≤ 21 dBm		(NOTES 2, 3)	
Carrier	dBc	-25+TT -20+TT	Output power > 11 dBm		Carrier frequency	
	An in han	-	$-13 \text{ dBm} \le \text{Output power} \le 11 \text{ dBm}$		(NOTES 4, 5)	
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub>- 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the</li> </ul>						
	carrier spacing between the CCs is not a multiple of RB. NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.					
	· ·=	are EIRP in beam pea				

# Table 6.4A.2.3.3.5-4: Test Requirements for in-band emissions for power class 4

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# 6.4A.2.3.4 In-band emissions for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

#### 6.4A.2.3.4.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

## 6.4A.2.3.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

## 6.4A.2.3.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

# 6.4A.2.3.4.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.4.4.1-1.

# Table 6.4A.2.3.4.4.1-1: Test Configuration Table for 5UL CA

	Default Conditions					
Test Env	Test Environment as specified in TS 38.508-1 [10]			Normal		
subclaus	e 4.1					
		ified in TS 38.508-		Low and	High range	
		lifferent CA bandw				
		Cs are mapped or				
		ording to Table 6.1-	·2.			
		ing as specified in				e CA configuration
		.2-1 and 5.5A.2-2 f		Highest a	aggregated BW of the	ne CA configuration
		pandwidth combina	ation sets			
	d by the UE.			1		
Test SC3	S as specified in	Table 5.3.5-1.	Tee	Lowest		
-				t Paramete	ers	
CA Co	onfiguration / Ag	gregated BW		nlink uration	Uplink Configuration	
Test ID	CC & Mapping	ChBw(MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)
						Inner_4RB_Left for PC2, PC3,
	PCC				DFT-s-OFDM	PC4
	100			/ <b>A</b>	PI/2 BPSK	Inner_16RB_Left_Region2 for PC1
1	SCC1	Default	N,	/A	-	-
	SCC2				-	-
	SCC3				-	-
	SCC4				-	-

	PCC			DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1		
2	SCC1			-	-		
	SCC2			-	-		
	SCC3			-	-		
	SCC4			-	-		
	PCC			CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1		
3	SCC1			-	-		
	SCC2			-	-		
	SCC3			-	-		
	SCC4			-	-		
	PCC			CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1		
4	SCC1			-	-		
	SCC2			-	-		
	SCC3			-	-		
	SCC4			-	-		
NOTE 1:	The specific co	onfiguration of eac	h RB allocation is def	ined in Table 6.1-1	for PC2, PC3 and PC4 or Table		
NOTE 2:	NOTE 2: CA Configuration Test cumulative aggregated BW settings are checked separately for each CA Configuration, which applicable aggregated channel bandwidths are specified in Table 5.5A.1-1						

# 6.4A.2.3.4.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.4.5-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix}$	+TT	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image dB -25+TT		-25+TT	Output power > 27 dBm		Image frequencies	
i = mage	GD	-20+TT	Output power ≤ 27 dBm		(NOTES 2, 3)	
Carrier	dBc	-25+TT	Output power > 17 dBm	Output power > 17 dBm		
leakage	UBC	-20+TT	4 dBm ≤ Output power ≤ 17 dBm		Carrier frequency (NOTES 4, 5)	

Table 6.4A.2.3.4.5-1: Test Requirements for in-band emissions for power class 1

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB. L <sub>CRR</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs. $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
NOTE 9:	carrier spacing between the CCs is not a multiple of RB. $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.
NOTE 10	: All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.4.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)	Applicable Frequencies		
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT	Output power > 16 dBm	Image frequencies		
Carrier		-20+TT -25+TT	Output power ≤ 16 dBm Output power > 6 dBm	(NOTES 2, 3) Carrier frequency		
leakage	dBc	-20+TT	-13 dBm ≤ Output power ≤ 6 dBm	(NOTES 4, 5)		
	n in-ban					
CANOTE 2: TH RI Pi th NOTE 3: Im NOTE 4: TH RI NOTE 5: TH th NOTE 6: L	<ul> <li>RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> </ul>					
	7: EVM is the limit for the modulation format used in the allocated RBs. 8: $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB} = 1$ or					
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the					
ca NOTE 9: P	carrier spacing between the CCs is not a multiple of RB. NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm. NOTE 10: All powers are EIRP in beam peak direction.					

Table 6.4A.2.3.4.5-2: Test Requirements for in-band emissions for power class 2

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.4.5-3 for power class 3 UEs.

Parameter description	Unit		Applicable Frequencies			
General	dB	max	$-25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right),$ $20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}},$ $-55.1 dBm - P_{RB}$	+TT	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image	dB	-25+TT	Output power > 10 dBm		Image frequencies	
	чь	-20+TT	Output power ≤ 10 dBm		(NOTES 2, 3)	
Carrier	dBc	-25+TT	Output power > 0 dBm		Carrier frequency	
	n in hon	-20+TT	$-13 \text{ dBm} \le \text{Output power} \le 0 \text{ dBm}$	tod PP. For apph quick I	(NOTES 4, 5)	
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub>- 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the</li> </ul>						
	carrier spacing between the CCs is not a multiple of RB. NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.					
	· ·=-	are EIRP in beam pea				

# Table 6.4A.2.3.4.5-3: Test Requirements for in-band emissions for power class 3

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For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.4.5-4 for power class 4 UEs.

Parameter description	Unit		Limit (NOTE 1)		
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 . 1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)	
IQ Image	dB	-25+TT	Output power > 21 dBm	Image frequencies (NOTES 2, 3)	
Corrier			-20+TT Output power ≤ 21 dBm		
Carrier leakage	dBc	-25+TT -20+TT	Output power > 11 dBm -13 dBm ≤ Output power ≤ 11 dBm	Carrier frequency (NOTES 4, 5)	

Table 6.4A.2.3.4.5-4: Test Requirements for in-band emissions for power class 4

NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub>- 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply.  $P_{RB}$  is defined in NOTE 9. The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated NOTE 2: RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD. NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency. NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs. NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB. NOTE 6: L<sub>CRR</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1). EVM is the limit for the modulation format used in the allocated RBs. NOTE 7: NOTE 8:  $\Delta_{RB}$  is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g.  $\Delta_{RB} = 1$  or  $\Delta_{_{RB}}$  = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB. NOTE 9:  $P_{RB}$  is the transmitted power per allocated RB, measured in dBm. NOTE 10: All powers are EIRP in beam peak direction.

# 6.4A.2.3.5 In-band emissions for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

### 6.4A.2.3.5.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

### 6.4A.2.3.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

### 6.4A.2.3.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

### 6.4A.2.3.5.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.5.4.1-1.

			Dofo	ut Conditi	ana		
Toot Env	ironmont on ono	ified in TS 20 E00		ult Conditions			
Test Environment as specified in TS 38.508-1 [10] subclause 4.1				Normal			
		vified in TS 38 508.	1 [10]	Low and High range			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth				LOW and	riigirrange		
classes, and PCC and SCCs are mapped onto							
physical frequencies according to Table 6.1-2.							
		ing as specified in	Ζ.	Lowesta	aareasted BW of th	ne CA configuration	
		.2-1 and 5.5A.2-2 f	or the			he CA configuration	
		pandwidth combina		riighest t	aggregated by or t	ne on comiguation	
	d by the UE.		001 3013				
	as specified in	Table 5 3 5-1		Lowest			
1031 000		14510 0.0.0 1.	Test	t Paramete	ers		
				nlink			
CA Co	onfiguration / Ag	gregated BW		uration	Up	link Configuration	
Test	& 33	ChBw(MHz)		ocation	Modulation	RB allocation (NOTE 1)	
ID	Mapping	•=,					
					DET OFDM	Inner_4RB_Left for PC2, PC3,	
	PCC				DFT-s-OFDM	PC4	
					PI/2 BPSK	Inner_16RB_Left_Region2 for	
4	8004					PC1	
1	SCC1 SCC2				-	-	
					-	-	
-	SCC3				-	-	
-	SCC4				-	-	
	SCC5				-	-	
	PCC					Inner_4RB_Right for PC2,	
					DFT-s-OFDM PI/2 BPSK	PC3, PC4	
					PI/Z DPSK	Inner_16RB_Right_Region2 for PC1	
2	SCC1				-	-	
2	SCC2				-		
	SCC3				-	-	
-						-	
-	SCC5					-	
	3005	Default	N	/A	-	Inner_4RB_Left for PC2, PC3,	
					CP-OFDM	PC4	
	PCC				QPSK	Inner_16RB_Left_Region2 for	
					GION	PC1	
3	SCC1				-	-	
5	SCC2	1			-	-	
ŀ	SCC3				-	-	
	SCC4				-	-	
ŀ	SCC5				-	-	
	0000					Inner_4RB_Right for PC2,	
					CP-OFDM	PC3, PC4	
	PCC				QPSK	Inner_16RB_Right_Region2 for	
						PC1	
4	SCC1	1			-	-	
•	SCC2				-	-	
ŀ	SCC3				-	-	
ŀ	SCC4	1			-	-	
SCC5							
NOTE 1		nfiguration of eac	h RB alloc	ation is de	fined in Table 6 1-	1 for PC2, PC3 and PC4 or Table	
	6.1-2 for PC1.	garadon or odo					
NOTE 2:		tion Test cumula	tive addre	egated BV	V settinas are ch	necked separately for each CA	
	Configuration	which applicable a	agregated	channel ba	andwidths are spec	ified in Table 5.5A.1-1	
			<u></u>				

Table 6.4A.2.3.5.4.1-1: To	est Configuration	Table for 6UL CA
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# 6.4A.2.3.5.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.5.5-1 for power class 1 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies	
General	dB	max	$ \begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT $	C	Any non-allocated RB in allocated omponent carrier and not allocated omponent carriers (NOTE 2)	
IQ Image	dB	-25+TT	Output power > 27 dBm	In	mage frequencies	
		-20+TT	Output power ≤ 27 dBm		(NOTES 2, 3)	
Carrier leakage	dBc	-25+TT -20+TT	Output power > 17 dBm 4 dBm $\leq$ Output power $\leq$ 17 dBm	(	Carrier frequency (NOTES 4, 5)	
	in-ban	-		For each such RB 1		
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (<i>P<sub>RB</sub></i> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. <i>P<sub>RB</sub></i> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB.</li> </ul>						
NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.						
NOTE 10: All	powers	s are EIRP in beam pea	k direction.			

# Table 6.4A.2.3.5.5-1: Test Requirements for in-band emissions for power class 1

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For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.5.5-2 for power class 2 UEs.

Parameter description	Unit	Limit (NOTE 1)		Applicable Frequencies
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT -20+TT	Output power > 16 dBm Output power ≤ 16 dBm	Image frequencies (NOTES 2, 3)
Carrier	dBc	-20+11 -25+TT	Output power > 6 dBm	Carrier frequency
leakage		-20+TT	-13 dBm ≤ Output power ≤ 6 dBm	(NOTES 4, 5)

Table 6.4A.2.3.5.5-2: Test Requirements for in-band emissions for power class 2

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.
	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.5.5-3 for power class 3 UEs.

Parameter description	Unit	Limit (NOTE 1)		Applicable Frequencies			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)			
IQ Image	dB	-25+TT	Output power > 10 dBm	Image frequencies			
Carrier	-	-20+TT -25+TT	Output power ≤ 10 dBm Output power > 0 dBm	(NOTES 2, 3) Carrier frequency			
leakage	dBc	-20+TT	-13 dBm ≤ Output power ≤ 0 dBm	(NOTES 4, 5)			
	n in-ban						
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).</li> <li>NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the</li> </ul>							
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the anocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB.						
	9: P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.						
NOTE 10: All powers are EIRP in beam peak direction.							

## Table 6.4A.2.3.5.5-3: Test Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.5.5-4 for power class 4 UEs.

Parameter description	Unit	Limit (NOTE 1)			Applicable Frequencies		
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix}$	+TT	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT	Output power > 21 dBm		Image frequencies		
•		-20+TT	Output power ≤ 21 dBm		(NOTES 2, 3)		
Carrier leakage	dBc	-25+TT -20+TT	Output power > 11 dBm -13 dBm ≤ Output power ≤ 11 dBn	0	Carrier frequency (NOTES 4, 5)		
	n in-han	-	imit is evaluated in each non-alloca				
			higher of ( $P_{RB}$ - 25 dB) and the power				
			i i i i i i i i i i i i i i i i i i i				
<ul> <li>Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> </ul>							
	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.						
			RB and the limit is expressed as a	ratio of measured powe	er in one non-allocated		
NOTE 5: T	<ul> <li>RB to the measured total power in all allocated RBs.</li> <li>5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> </ul>						
	EVM is the limit for the modulation format used in the allocated RBs.						
	E 8: $\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB} = 1$ or						
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the						
	carrier spacing between the CCs is not a multiple of RB.						
NOTE 9: $P_{RB}$ is the transmitted power per allocated RB, measured in dBm.							
NOTE 10: All powers are EIRP in beam peak direction.							

# Table 6.4A.2.3.5.5-4: Test Requirements for in-band emissions for power class 4

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# 6.4A.2.3.6 In-band emissions for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

#### 6.4A.2.3.6.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

## 6.4A.2.3.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.4A.2.3.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

### 6.4A.2.3.6.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.6.4.1-1.

## Table 6.4A.2.3.6.4.1-1: Test Configuration Table for 7UL CA

			Defau	ult Conditi	ons		
	Test Environment as specified in TS 38.508-1 [10]						
subclause 4.1							
Test Frequencies as specified in TS 38.508-1 [10]				Low and	High range		
subclause [4.3.1.2.3] for different CA bandwidth							
	classes, and PCC and SCCs are mapped onto						
		ording to Table 6.1-	-2.				
		ing as specified in		Lowest a	ggregated BW of th	e CA configuration	
		.2-1 and 5.5A.2-2 f		Highest a	aggregated BW of the	ne CA configuration	
		pandwidth combina	ation sets				
	supported by the UE.						
Test SCS	Test SCS as specified in Table 5.3.5-1.				Lowest		
			Test	t Paramete	ers		
CA Co	CA Configuration / Aggregated BW Config			nlink Uplink Configuration		link Configuration	
Test ID	CC & Mapping	ChBw(MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)	
						Inner_4RB_Left for PC2, PC3,	
	PCC				DFT-s-OFDM	PC4	
	FCC				PI/2 BPSK	Inner_16RB_Left_Region2 for	
						PC1	
1	SCC1	Default	N	/A	-	-	
1	SCC2	Delault	IN,	/A	-	-	
	SCC3				-	-	
	SCC4				-	-	
	SCC5				-	-	
	SCC6				-	-	

	PCC			DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1
2	SCC1			-	-
2	SCC2			-	-
	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
	PCC			CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1
3	SCC1			-	-
	SCC2			-	-
	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
	PCC			CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1
	SCC1			-	-
4	SCC2			-	-
	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
NOTE 1:	The specific co 6.1-2 for PC1.	infiguration of eacl	h RB allocation is def	ined in Table 6.1-1	for PC2, PC3 and PC4 or Table
NOTE 2:	CA Configurat				ecked separately for each CA fied in Table 5.5A.1-1

## 6.4A.2.3.6.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.6.5-1 for power class 1 UEs.

Parameter description	Unit		Applicable Frequencies	
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB -25+TT		Output power > 27 dBm	Image frequencies
		-20+TT	Output power ≤ 27 dBm	(NOTES 2, 3)
Carrier	dBc	-25+TT	Output power > 17 dBm	Carrier frequency
leakage	ubc	-20+TT	4 dBm ≤ Output power ≤ 17 dBm	(NOTES 4, 5)

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. $P_{BB}$ is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated
	RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
	: All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.6.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)		Applicable Frequencies		
General	eral dB $\max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} +TT$						
IQ Image	dB	-25+TT -20+TT	Output power > 16 dBm		Image frequencies		
Carrier leakage	Carrier $-20+11$ Output power $\le 16$ dBmCarrier $-25+TT$ Output power $> 6$ dBm				(NOTES 2, 3) Carrier frequency (NOTES 4, 5)		
<ul> <li>NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (<i>P<sub>RB</sub></i> - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. <i>P<sub>RB</sub></i> is defined in NOTE 9.</li> <li>NOTE 2: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.</li> <li>NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.</li> <li>NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs.</li> <li>NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.</li> <li>NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated RBs.</li> <li>NOTE 8: Δ<sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ<sub>RB</sub> = 1 or Δ<sub>RB</sub> = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB.</li> <li>NOTE 9: <i>P<sub>RB</sub></i> is the transmitted power per allocated RB, measured in dBm.</li> </ul>							

### Table 6.4A.2.3.6.5-2: Test Requirements for in-band emissions for power class 2

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.6.5-3 for power class 3 UEs.

IQ Image     OB       Carrier     dBc       leakage     dBc       NOTE 1:     An in-band emission requirement is calc       Carrier leakage) that the measurement     Carrier leakage) that the measurement       NOTE 2:     The measurement       RB to the measurement     Pi/2 BPSK with Spectrum the measured power	$\max \begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 \cdot 1 dBm - P_{RB} \end{bmatrix} + TT$ $25 + TT \qquad Output power > 10 dBm$ $20 + TT \qquad Output power \le 10 dBm$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)						
IQ Image     OB       Carrier     dBc       leakage     dBc       NOTE 1:     An in-band emission requirement is calc       Carrier leakage) that the measurement     Carrier leakage) that the measurement       NOTE 2:     The measurement       RB to the measurement     Pi/2 BPSK with Spectrum the measured power								
Carrier leakage NOTE 1: An in-band emission requirement is calc Carrier leakage) that NOTE 2: The measurement RB to the measure Pi/2 BPSK with Spot the measured power		Image frequencies (NOTES 2, 3)						
NOTE 1: An in-band emission requirement is calc Carrier leakage) the NOTE 2: The measurement RB to the measure Pi/2 BPSK with Spo the measured powe	$25+TT$ Output power > 0 dBm $20+TT$ -13 dBm $\leq$ Output power $\leq$ 0 dBm	Carrier frequency (NOTES 4, 5)						
RB to the measure NOTE 5: The applicable freq the two RBs immed NOTE 6: $L_{CRB}$ is the Transmi NOTE 7: EVM is the limit for NOTE 8: $\Delta_{RB}$ is the starting f $\Delta_{RB} = -1$ for the first	NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. $P_{RB}$ is defined in NOTE 9.							

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.6.5-4 for power class 4 UEs.

Parameter description	Unit		Applicable Frequencies	
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 21 dBm	Image frequencies
	Carrier         dBc         -20+TT           Order         -25+TT         -25+TT		Output power ≤ 21 dBm	(NOTES 2, 3)
			Output power > 11 dBm	Carrier frequency
leakage	abo	-20+TT	-13 dBm ≤ Output power ≤ 11 dBm	(NOTES 4, 5)

Table 6.4A.2.3.6.5-4: Test Requirements for in-band emissions for power class 4

NOTE 1: An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of (P<sub>RB</sub>- 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. P<sub>RB</sub> is defined in NOTE 9. The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated NOTE 2: RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD. NOTE 3: Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency. NOTE 4: The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured total power in all allocated RBs. NOTE 5: The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB. NOTE 6: L<sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1). NOTE 7: EVM is the limit for the modulation format used in the allocated RBs. NOTE 8:  $\Delta_{RB}$  is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g.  $\Delta_{RB} = 1$  or  $\Delta_{_{BB}}$  = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the carrier spacing between the CCs is not a multiple of RB. NOTE 9:  $P_{RB}$  is the transmitted power per allocated RB, measured in dBm. NOTE 10: All powers are EIRP in beam peak direction.

## 6.4A.2.3.7 In-band emissions for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- The test procedure is incomplete due to that power window for CA is TBD
- Measurement Uncertainty and Test Tolerance are FFS.
- Testing of the general in-band emission requirement and if yes at which UE Tx power level and with which relaxation applied to the requirement is FFS.

#### 6.4A.2.3.7.1 Test purpose

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

The purpose of this test is to exercise the UE transmitter to verify its modulation quality in terms of in-band emissions.

#### 6.4A.2.3.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

#### 6.4A.2.3.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.4A.2.3.0.

#### 6.4A.2.3.7.4 Test description

Same as in clause 6.4A.2.3.1.4 with following exceptions:

- Instead of Table 6.4A.2.3.1.4.1-1 → use Table 6.4A.2.3.7.4.1-1.

			Defau	ult Conditi	ons		
	Test Environment as specified in TS 38.508-1 [10] subclause 4.1				Normal		
	Test Frequencies as specified in TS 38.508-1 [10]				High range		
	subclause [4.3.1.2.3] for different CA bandwidth						
	classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.						
			-2.				
		ing as specified in				e CA configuration	
		.2-1 and 5.5A.2-2 f		Hignest a	iggregated BVV of th	ne CA configuration	
	d by the UE.	pandwidth combina	ation sets				
	S as specified in	Table 5 3 5-1		Lowest			
1031 300			Test	t Paramete	ers		
	Dow			nlink			
CA Co	onfiguration / Ag	gregated BW		uration Uplink Configuration			
Test ID	CC & Mapping	ChBw(MHz)	RB allo	ocation	Modulation	RB allocation (NOTE 1)	
						Inner_4RB_Left for PC2, PC3,	
	PCC				DFT-s-OFDM		
					PI/2 BPSK	Inner_16RB_Left_Region2 for PC1	
	SCC1				-	-	
1	SCC2	Default	N	/A	-	-	
	SCC3				-	-	
	SCC4				-	-	
	SCC5				-	-	
	SCC6				-	-	
	SCC7				-	-	

## Table 6.4A.2.3.7.4.1-1: Test Configuration Table for 8UL CA

	PCC			DFT-s-OFDM PI/2 BPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1
	SCC1			-	-
2	SCC2			-	-
	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
	SCC7			-	-
	PCC			CP-OFDM QPSK	Inner_4RB_Left for PC2, PC3, PC4 Inner_16RB_Left_Region2 for PC1
3	SCC1			-	-
	SCC2			-	-
· ·	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
	SCC7			-	-
	PCC			CP-OFDM QPSK	Inner_4RB_Right for PC2, PC3, PC4 Inner_16RB_Right_Region2 for PC1
	SCC1			-	-
4	SCC2			-	-
	SCC3			-	-
	SCC4			-	-
	SCC5			-	-
	SCC6			-	-
	SCC7			-	-
NOTE 1:	The specific co 6.1-2 for PC1.	infiguration of each	h RB allocation is def	fined in Table 6.1-1	I for PC2, PC3 and PC4 or Table
NOTE 2:					ecked separately for each CA ified in Table 5.5A.1-1

## 6.4A.2.3.7.5 Test requirement

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.7.5-1 for power class 1 UEs.

Parameter description	Unit		Applicable Frequencies	
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)
IQ Image	dB	-25+TT	Output power > 27 dBm	Image frequencies
is inage	чD	-20+TT	Output power ≤ 27 dBm	(NOTES 2, 3)
Carrier	dBc	-25+TT	Output power > 17 dBm	Carrier frequency
leakage	UBC	-20+TT	4 dBm ≤ Output power ≤ 17 dBm	(NOTES 4, 5)

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated
	RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
NOTE 7:	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
NOTE 10	: All powers are EIRP in beam peak direction.

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.7.5-2 for power class 2 UEs.

Parameter description	Unit		Limit (NOTE 1)				
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-alloc RB in alloca component c and not alloc component ca (NOTE 2	ated arrier cated arriers		
IQ Image	dB	-25+TT	Output power > 16 dBm	Image freque			
-		-20+TT	Output power ≤ 16 dBm	(NOTES 2,			
Carrier leakage	dBc	-25+TT -20+TT	Output power > 6 dBm -13 dBm $\leq$ Output power $\leq$ 6 dBm	Carrier frequ (NOTES 4,			
	in-han	-	imit is evaluated in each non-allocated RE				
			higher of ( $P_{RB}$ - 25 dB) and the power sum				
		akage) that apply. $P_{RB}$ is					
RI Pi							
			specified in relation to either UL or DL ca	rier frequency.			
			RB and the limit is expressed as a ratio of		ocated		
		measured total power i					
			s limit are those that are enclosed in the F		, or in		
			t to the DC frequency but excluding any a				
			Ith for kth allocated component carrier (se	e Figure 5.3.3-1).			
	NOTE 7: EVM is the limit for the modulation format used in the allocated RBs.						
			t between the allocated RB and the meas				
			outside of the allocated bandwidth), and n	ay take non-integer values when	the		
	carrier spacing between the CCs is not a multiple of RB.						
			allocated RB, measured in dBm.				
NOTE 10: AI	powers	s are EIRP in beam pea	k direction.				

## Table 6.4A.2.3.7.5-2: Test Requirements for in-band emissions for power class 2

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage in Table 6.4A.2.3.7.5-3 for power class 3 UEs.

Parameter description	Unit		Applicable Frequencies			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55.1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT -20+TT	Output power > 10 dBm Output power ≤ 10 dBm	Image frequencies (NOTES 2, 3)		
Carrier leakage	Carrier -25+TT Output power > 0 dBm		Carrier frequency (NOTES 4, 5)			
leakage       use       -20+TT       -13 dBm ≤ Output power ≤ 0 dBm       (NOTES 4, 5)         NOTE 1:       An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply. $P_{RB}$ is defined in NOTE 9.         NOTE 2:       The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For Pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.         NOTE 3:       Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.         NOTE 4:       The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in all allocated RBs.         NOTE 5:       The applicable frequencies for this Imit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.         NOTE 6:       L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).         NOTE 7:       EVM is the limit for the modulation format used in the allocated RBs.         NOTE 8:       Δ <sub>RB</sub> is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. Δ <sub>RB</sub> = 1 or $Δ_{RB} = -1$ for the firs						
		s are EIRP in beam pea	allocated RB, measured in dBm. k direction.			

## Table 6.4A.2.3.7.5-3: Test Requirements for in-band emissions for power class 3

For power ID1 and ID2, the averaged in-band emissions result, derived in Annex E.4.3 shall not exceed the corresponding values for IQ Image and Carrier Leakage Table 6.4A.2.3.7.5-4 for power class 4 UEs.

Parameter description	Unit		Limit (NOTE 1)			
General	dB	max	$\begin{bmatrix} -25 - 10 \cdot \log_{10} \left( \frac{N_{RB}}{L_{CRB}} \right), \\ 20 \cdot \log_{10} (EVM) - 5 \cdot \frac{( \Delta_{RB}  - 1)}{L_{CRB}}, \\ -55 .1 dBm - P_{RB} \end{bmatrix} + TT$	Any non-allocated RB in allocated component carrier and not allocated component carriers (NOTE 2)		
IQ Image	dB	-25+TT -20+TT	Output power > 21 dBm Output power ≤ 21 dBm	Image frequencies (NOTES 2, 3)		
Carrier leakage	Carrier dBc -25+TT		Output power > 11 dBm -13 dBm ≤ Output power ≤ 11 dBm	Carrier frequency (NOTES 4, 5)		

Table 6.4A.2.3.7.5-4: Test Requirements for in-band emissions for power class 4

NOTE 1:	An in-band emissions combined limit is evaluated in each non-allocated RB. For each such RB, the minimum requirement is calculated as the higher of ( $P_{RB}$ - 25 dB) and the power sum of all limit values (General, IQ Image or
	Carrier leakage) that apply. P <sub>RB</sub> is defined in NOTE 9.
NOTE 2:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated RB to the measured average power per allocated RB, where the averaging is done across all allocated RBs. For pi/2 BPSK with Spectrum Shaping, the limit is expressed as a ratio of measured power in one non-allocated RB to the measured power in the allocated RB with highest PSD.
NOTE 3:	Image frequencies for UL CA are specified in relation to either UL or DL carrier frequency.
NOTE 4:	The measurement bandwidth is 1 RB and the limit is expressed as a ratio of measured power in one non-allocated
	RB to the measured total power in all allocated RBs.
NOTE 5:	The applicable frequencies for this limit are those that are enclosed in the RBs containing the DC frequency, or in the two RBs immediately adjacent to the DC frequency but excluding any allocated RB.
NOTE 6:	L <sub>CRB</sub> is the Transmission Bandwidth for kth allocated component carrier (see Figure 5.3.3-1).
	EVM is the limit for the modulation format used in the allocated RBs.
NOTE 8:	$\Delta_{RB}$ is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g. $\Delta_{RB}$ = 1 or
	$\Delta_{RB}$ = -1 for the first adjacent RB outside of the allocated bandwidth), and may take non-integer values when the
	carrier spacing between the CCs is not a multiple of RB.
NOTE 9:	P <sub>RB</sub> is the transmitted power per allocated RB, measured in dBm.
	: All powers are EIRP in beam peak direction.

6.4A.2.4 EVM equalizer spectrum flatness for CA

FFS.

6.4A.2.5 EVM spectral flatness for pi/2 BPSK modulation with spectrum shaping for CA

FFS.

# 6.4D Transmit signal quality for UL MIMO

## 6.4D.3 Time alignment error for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation.
- Test config table is still FFS.
- Test tolerance is FFS
- Applicability of UBF of single UL is FFS
- Applicability of Beam peak of single UL is FFS

### 6.4D.3.1 Test purpose

To verify that the error of time alignment in UL MIMO does not exceed the range prescribed by the specified UL MIMO Time Alignment Error (TAE) and tolerance.

An excess time alignment error has the possibility to interfere to other channels or other systems and decrease UL MIMO performance because of the timing unsynchronization.

### 6.4D.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that support UL MIMO.

## 6.4D.3.3 Minimum conformance requirements

For UE(s) with multiple physical antenna ports supporting UL MIMO, this requirement applies to frame timing differences between transmissions on multiple physical antenna ports in the codebook transmission scheme.

The time alignment error (TAE) is defined as the average frame timing difference between any two transmissions on different physical antenna ports.

For UE(s) with multiple physical antenna ports, the Time Alignment Error (TAE) shall not exceed 130 ns.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.4D.3.

## 6.4D.3.4 Test description

## 6.4D.3.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of test channel bandwidth and sub-carrier spacing, are shown in table 6.4D.3.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 6.4D.3.4.1-1: Test Configuration Table

FFS

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channels are set according to Table 6.4D.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.4D.3.4.3.

#### 6.4D.3.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.4D.3.4.1-1. Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.
- 2. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE until the UE transmits at P<sub>UMAX</sub> level. Allow at least 200ms starting from the first TPC Command for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition TxRx.

5. Measure the timing of one sub-frame at each physical antenna port.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

## 6.4D.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

## 6.4D.3.5 Test requirement

For UE(s) with multiple physical antenna ports, the Time Alignment Error (TAE) shall not exceed 130 + TT ns.

## Table 6.4D.3.5-1: Test Tolerance (Time alignment error for UL MIMO)

Test Tolerance	
FFS	

FFS.

# 6.5 Output RF spectrum emissions

Unwanted emissions are divided into "Out-of-band emission" and "Spurious emissions" in 3GPP RF specifications. This notation is in line with ITU-R recommendations such as SM.329 [7] and the Radio Regulations [TBD].

ITU defines:

Out-of-band emission = Emission on a frequency or frequencies immediately outside the necessary bandwidth which results from the modulation process, but excluding spurious emissions.

Spurious emission = Emission on a frequency, or frequencies, which are outside the necessary bandwidth and the level of which may be reduced without affecting the corresponding transmission of information. Spurious emissions include harmonic emissions, parasitic emissions, intermodulation products and frequency conversion products but exclude out-of-band emissions.

Unwanted emissions = Consist of spurious emissions and out-of-band emissions.

The UE transmitter spectrum emission consists of the three components; the occupied bandwidth (channel bandwidth), the Out Of Band (OOB) emissions and the far out spurious emission domain.

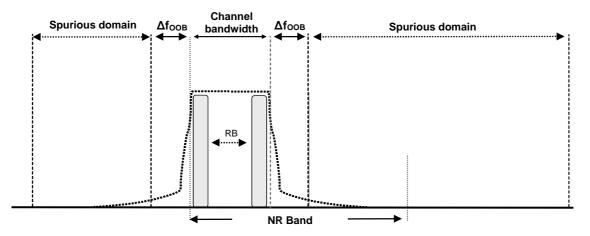


Figure 6.5-1: Transmitter RF spectrum

## 6.5.1 Occupied bandwidth

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty FFS.

#### 6.5.1.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits

#### 6.5.1.2 Test applicability

This test applies to all types of NR UE release 15 and forward.

#### 6.5.1.3 Minimum conformance requirements

Occupied bandwidth is defined as the bandwidth containing 99 % of the total integrated mean power of the transmitted spectrum on the assigned channel. The occupied bandwidth for all transmission bandwidth configurations (Resources Blocks) shall be less than the channel bandwidth specified in Table 6.5.1.3-1.

The occupied bandwidth is defined as a directional requirement. The requirement is verified in beam locked mode with the test metric of OBW (Link=TX beam peak direction, Meas=Link angle).

	Occupied channel bandwidth / Channel bandwidth50100200400MHzMHzMHzMHz			
Channel bandwidth (MHz)	50	100	200	400

 Table 6.5.1.3-1: Occupied channel bandwidth

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5.1.

#### 6.5.1.4 Test description

#### 6.5.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.5.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initial Conditions						
Test Enviro	onment as specified in TS 38.508-1 [10]	Normal					
clause 4.1							
Test Frequencies as specified in TS 38.508-1 [10] clause 4.3.1		Low range, Mid range, High range					
Test Channel Bandwidths as specified in TS 38.508-1 [10] clause 4.3.1		All					
	as specified in Table 5.3.5-1	Lowest					
	Т	est Parameters					
Test ID	Downlink Configuration	Uplink Configuration					
	N/A for occupied bandwidth test case	Modulation	RB allocation (NOTE 1)				
1	INA IOI Occupied bandwidth test case	DFT-s-OFDM QPSK	Outer_full				
	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and clause A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.1.4.3

#### 6.5.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure the EIRP spectrum distribution within 1.5-times or more frequency range over the requirement for Occupied Bandwidth specification centring on the current carrier frequency. The characteristics of the filter shall be approximately Gaussian (typical spectrum analyser filter). The measuring duration is one active uplink subframe. EIRP is captured from both polarizations, theta and phi.
- 6. Calculate the total EIRP from both polarizations, theta and phi, within the range of all frequencies measured in step 4 and save this value as "Total EIRP". EIRP measurement procedure is defined in Annex K.
- 7. Identify the measurement window whose centre is aligned on the centre of the channel for which the sum of the power measured in theta and phi polarization is 99% of the "Total EIRP".
- 8. The "Occupied Bandwidth" is the width of the measurement window obtained in step 6.

#### 6.5.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

6.5.1.5 Test requirement

The measured Occupied Bandwidth shall not exceed values in Table 6.5.1.5-1.

	Occupied channel bandwidth / Channel bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
Channel bandwidth (MHz)	50	100	200	400

#### Table 6.5.1.5-1: Occupied channel bandwidth

## 6.5.2 Out of band emission

The Out of band emissions are unwanted emissions immediately outside the assigned channel bandwidth resulting from the modulation process and non-linearity in the transmitter but excluding spurious emissions. This out of band emission limit is specified in terms of a spectrum emission mask and an Adjacent Channel Leakage power Ratio. Additional requirements to protect specific bands are also considered.

The requirements in clause 6.5.2.1 only apply when both UL and DL of a UE are configured for single CC operation, and they are of the same bandwidth. For a UE that is configured for single CC operation with different channel bandwidths in UL and DL, the requirements in clause 6.5A.2.1 apply.

All out of band emissions for range 2 are TRP.

## 6.5.2.1 Spectrum Emission Mask

## 6.5.2.1.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth.

## 6.5.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

## 6.5.2.1.3 Minimum conformance requirements

The spectrum emission mask of the UE applies to frequencies ( $\Delta f_{OOB}$ ) starting from the ± edge of the assigned NR channel bandwidth. For frequencies offset greater than  $F_{OOB}$  as specified in Table 6.5.2.1-1 the spurious requirements in clause 6.5.3 are applicable.

The power of any UE emission shall not exceed the levels specified in Table 6.5.2.1.3-1 for the specified channel bandwidth. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

Spec	Spectrum emission limit (dBm)/ Channel bandwidth							
<u></u> Δf <sub>ООВ</sub> (MHz)	50 MHz	100 MHz	200 MHz	400 MHz	Measurement bandwidth			
± 0-5	-5	-5	-5	-5	1 MHz			
± 5-10	-13	-5	-5	-5	1 MHz			
± 10-20	-13	-13	-5	-5	1 MHz			
± 20-40	-13	-13	-13	-5	1 MHz			
± 40-100	-13	-13	-13	-13	1 MHz			
± 100-200		-13	-13	-13	1 MHz			
± 200-400			-13	-13	1 MHz			
± 400-800				-13	1 MHz			

Table 6.5.2.1.3-1: General NR spectrum emission mask for Range 2.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5.2.1.

### 6.5.2.1.4 Test description

### 6.5.2.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.5.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initial Co	onditions	
subclause 4.		Normal	
Test Frequer subclause 4.	ncies as specified in TS 38.508-1 [10] 3.1	Mid range	
Test Channe subclause 4.	Bandwidths as specified in TS 38.508-1 [10] 3.1	Lowest, Mid, Highest	
Test SCS as	specified in Table 5.3.5-1	Lowest, Highest	
		rameters	
Test ID	Downlink Configuration		nfiguration
	N/A for Spectrum Emission Mask test case	Modulation	RB allocation (NOTE 1)
1		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Left
2		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right
3		DFT-s-OFDM PI/2 BPSK	Outer_Full
4		DFT-s-OFDM QPSK	Outer_1RB_Left
5		DFT-s-OFDM QPSK	Outer_1RB_Right
6		DFT-s-OFDM QPSK	Outer_Full
7		DFT-s-OFDM 16 QAM	Outer_1RB_Left
8		DFT-s-OFDM 16 QAM	Outer_1RB_Right
9		DFT-s-OFDM 16 QAM	Outer_Full
10		DFT-s-OFDM 64 QAM	Outer_1RB_Left
11		DFT-s-OFDM 64 QAM	Outer_1RB_Right
12		DFT-s-OFDM 64 QAM	Outer_Full
13		CP-OFDM QPSK	Outer_1RB_Left
14		CP-OFDM QPSK	Outer_1RB_Right
15		CP-OFDM QPSK	Outer_Full
fo	he specific configuration of each RF allocation is r PC1. I test points in this table must also exist in table		

#### Table 6.5.2.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and clause A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.2.1.4.3

#### 6.5.2.1.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5.2.1.4.2-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.

- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure the TRP of the transmitted signal with a measurement filter of bandwidths according to table 6.5.2.1.1.5-1. The centre frequency of the filter shall be stepped in continuous steps according to the same table. TRP shall be recorded for each step. The measurement period shall capture the active time slots. Total radiated power is measured according to TRP measurement procedure defined in Annex K. The measurement grid used for TRP measurement defined in Annex M. TRP is calculated considering both polarizations, theta and phi.
- NOTE 1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.5.2.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.5.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5.2.1.5 Test requirement

The measured TRP of any UE emission derived in step 4, shall fulfil requirements in Table.6.5.2.1.5-1.

Table 6.5.2.1.5-1: General NR spectrum	emission mask for Range 2
--	---------------------------

Spectrum emission limit (dBm)/ Channel bandwidth						
Δfoob	50	100	200	400	Measurement	
(MHz)	MHz	MHz	MHz	MHz	bandwidth	
± 0-5	-5 +	-5 + TT	-5 + TT	-5 + TT	1 MHz	
	TT					
± 5-10	-13 +	-5 + TT	-5 + TT	-5 + TT	1 MHz	
	TT					
± 10-20	-13 +	-13 +	-5 + TT	-5 + TT	1 MHz	
	TT	TT				
± 20-40	-13 +	-13 +	-13 +	-5 + TT	1 MHz	
	TT	TT	TT			
± 40-100	-13 +	-13 +	-13 +	-13 +	1 MHz	
	TT	TT	TT	TT		
± 100-200		-13 +	-13 +	-13 +	1 MHz	
		TT	TT	TT		
± 200-400			-13 +	-13	1 MHz	
			TT	+TT		
$\pm 400-800$				-13 +	1 MHz	
				TT		
			and chann	el bandwid	th is specified in	
	Table 6.5.2.1.5-1a					
	At the boundary of spectrum emission limit, the first and last					
measurement position with a 1 MHz filter is the inside of					he inside of	
+0.5MHz and -0.5MHz, respectively.						
NOTE 3: The measurements are to be performed above the edge of the channel and below the lower edge of t						
	•	channel an	d below the	e lower edg	ge of the	
ch	annel.					

Table 6.5.2.1.5-1a: Test Tolerance (Spectrum en
---

Test Metric	23.45GHz ≤ f ≤ 32.125GHz	32.125GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

NOTE: As a general rule, the resolution bandwidth of the measuring equipment should be equal to the measurement bandwidth. However, to improve measurement accuracy, sensitivity and efficiency, the resolution bandwidth may be smaller than the measurement bandwidth. When the resolution bandwidth is smaller than the measurement bandwidth, the result should be integrated over the measurement bandwidth in order to obtain the equivalent noise bandwidth of the measurement bandwidth.

#### 6.5.2.2 Void

## 6.5.2.3 Adjacent channel leakage ratio

Editor's note: The following aspects are either missing or not yet determined:

- Test configuration, Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2, and 4.

## 6.5.2.3.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR).

#### 6.5.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.5.2.3.3 Minimum conformance requirements

Adjacent Channel Leakage power Ratio (ACLR) is the ratio of the filtered mean power centred on the assigned channel frequency to the filtered mean power centred on an adjacent channel frequency. ACLR requirement is specified for a scenario in which adjacent carrier is another NR channel.

NR Adjacent Channel Leakage power Ratio (NR<sub>ACLR</sub>) is the ratio of the filtered mean power centred on the assigned channel frequency to the filtered mean power centred on an adjacent channel frequency at nominal channel spacing. The assigned NR channel power and adjacent NR channel power are measured with rectangular filters with measurement bandwidths specified in Table 6.5.2.3.3-1.

If the measured adjacent channel power is greater than -35 dBm then the NR<sub>ACLR</sub> shall be higher than the value specified in Table 6.5.2.3.3-1. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

	Channel bandwidth / NR <sub>ACLR</sub> / Measurement bandwidth				
	50 MHz	100 MHz	200 MHz	400 MHz	
NR <sub>ACLR</sub> for band n257, n258, n261	17 dB	17 dB	17 dB	17 dB	
NR <sub>ACLR</sub> for band n260	16 dB	16 dB	16 dB	16 dB	
NR channel Measurement bandwidth (MHz)	47.58	95.16	190.20	380.28	
Adjacent channel centre frequency offset [MHz]	+50 / -50	+100 / -100	+200 / -200	+400 / -400	

## Table 6.5.2.3.3-1: General requirements for NR<sub>ACLR</sub>

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5.2.3.1.

## 6.5.2.3.4 Test description

## 6.5.2.3.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.5.2.3.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Default Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			38.508-1 [10]	Normal			
Test Frequencies as specified in TS 38.508-1 [10]			38.508-1 [10]	Low range, High range			
	ause 4.3.1						
	Channel Ba		•	ed in TS	Lowest, Mid, Highest		
	8-1 [10] su						
Test S	SCS as sp	ecified in	Table 5.3.8		Lowest, Highest		
<b>T</b>				Test Param			
Test ID	Freq	ChBw	SCS	Downlink	Uplink Config	uration	
טו		Default	Default	Configuration N/A for	Madulatian	DD alla sation	
		Default	Default	Adjacent	Modulation	RB allocation (NOTE 1)	
1	Low			Channel	DFT-s-OFDM PI/2 BPSK	Outer 1RB Left	
2	High			Leakage Ratio	DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right	
3	Default			test case	DFT-s-OFDM PI/2 BPSK	Outer Full	
4	Low				DFT-s-OFDM QPSK	Outer_1RB_Left	
5	High				DFT-s-OFDM QPSK	Outer_1RB_Right	
6	Default				DFT-s-OFDM QPSK	Outer_Full	
7	7 Low		DFT-s-OFDM 16 QAM	Outer_1RB_Left			
8	High				DFT-s-OFDM 16 QAM	Outer_1RB_Right	
9	Default				DFT-s-OFDM 16 QAM	Outer_Full	
10	Default				DFT-s-OFDM 64 QAM	Outer_Full	
11	Low				CP-OFDM QPSK	Outer_1RB_Left	
12	High				CP-OFDM QPSK	Outer_1RB_Right	
13	Default				CP-OFDM QPSK	Outer_Full	
NOTE					ation is defined in Table 6.1-	1 for PC2, PC3	
NOTE			ble 6.1-2 fo				
NOTE				be skipped for FR2 Hz Channel Bandy			
				b 200MHz Chann			
				00MHz Channel E			
NOTE		· -			n table 6.2.2.4.1-1, table 6.2.	2.4.1-2. table	
		.4.1-3 (MF					
0.2.2.4.1 0 (WEIX).							

Table 6.5.2.3.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and section A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.2.3.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.2.3.4.3

#### 6.5.2.3.4.2 Test procedure

- 1. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5.2.3.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure EIRP of the transmitted signal in the Tx beam peak direction for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.5.2.3.5-1. EIRP measurement procedure defined in Annex K. EIRP is calculated considering both polarizations, theta and phi.
- 6. Measure EIRP of the first NR adjacent channel on both lower and upper side of the assigned NR channel, respectively using a rectangular measurement filter with bandwidths according to Table 6.5.2.3.5-1. EIRP measurement procedure defined in Annex K. EIRP is calculated considering both polarizations, theta and phi.
- 7. Calculate the ratios of the power between the values measured in step 5 over step 6 for lower and upper NR ACLR, respectively.
- NOTE 1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.5.2.3.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.5.2.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5.2.3.5 Test requirement

The measured NR ACLR, derived in step 7, shall be higher than the limits in table 6.5.2.3.5-1.

	Channel bandwidth / NR <sub>ACLR</sub> / Measurement bandwidth				
	50 MHz	100 MHz	200 MHz	400 MHz	
NR <sub>ACLR</sub> for band n257, n258, n261	17 - TT – R dB	17 - TT – R dB	17 - TT – R dB	17 - TT – R dB	
NR <sub>ACLR</sub> for band n260	16 - TT dB	16 - TT dB	16 - TT dB	16 - TT dB	
NR channel Measurement bandwidth (MHz)	47.58	95.16	190.20	380.28	
NR channel Measurement bandwidth	47.58 MHz	95.16 MHz	190.20 MHz	380.28 MHz	
Adjacent channel centre frequency offset [MHz]         +50 / -50         +100 / / -100         +200 / / / -200         +400 / / / -400					
NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5.2.3.5-1a NOTE 2: R for each frequency, channel bandwidth and test point is specified in Table 6.5.2.3.5-1b					

Table 6.5.2.3.5-1: General requirements for NR<sub>ACLR</sub>

Test Metric	Channel bandwidth	23.45GHz ≤ f ≤ 30.3GHz	30.3GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)	50 MHz	4.66 dB	4.96 dB
	100 MHz	4.96 dB	4.96 dB
	200 MHz	4.96 dB	4.96 dB
	400 MHz	4.96 dB	4.96 dB

Table 6 5 2 3 5-1a: Test Tolerance	e (Adjacent channel leakage ratio)
	, (Aujacent channel leakage ratio)

#### Table 6.5.2.3.5-1b: Relaxation due to testability limit (Adjacent channel leakage ratio)

		Channel bandwidth / NR <sub>ACLR</sub> / Measurement bandwidth					
	Test ID	50 MHz	100 MHz	200 MHz	400 MHz		
NR <sub>ACLR</sub> for band n257, n258, n261	1-6	0	0	0	0		
	7	0	0	0	1.5		
	8	0	0	0	1.5		
	9	0	0	0	1.5		
	10	0	0	0.5	3.5		
	11	0	0	0	2		
	12	0	0	0	2		
	13	0	0	0	2		
NOTE 1: Relaxation value is derived by Max(0, MPR for test point – Maximum Testable MPR), where							
Maximum Testable MPR is 9.5dB(50MHz CBW), 7.0dB (100MHz CBW), 5.0dB (200MHz CBW) and 3.0dB (400MHz CBW) for FR2a.							

## 6.5.3 Spurious emissions

Spurious emissions are emissions which are caused by unwanted transmitter effects such as harmonics emission, parasitic emissions, intermodulation products and frequency conversion products, but exclude out of band emissions. The spurious emission limits are specified in terms of general requirements in line with SM.329 [7] and *NR* operating band requirement to address UE co-existence. Spurious emissions are measured as TRP.

To improve measurement accuracy, sensitivity and efficiency, the resolution bandwidth may be smaller than the measurement bandwidth. When the resolution bandwidth is smaller than the measurement bandwidth, the result should be integrated over the measurement bandwidth in order to obtain the equivalent noise bandwidth of the measurement bandwidth.

## 6.5.3.1 Transmitter Spurious emissions

- Editor's Note: This clause is complete for Band n257, n258 and n261 and PC3. The following aspects of the clause are for future consideration:
- TRP Measurement uncertainty is TBD for above 66GHz.

#### 6.5.3.1.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

#### 6.5.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.5.3.1.3 Minimum conformance requirements

Unless otherwise stated, the spurious emission limits apply for the frequency ranges that are more than  $F_{OOB}$  (MHz) in Table 6.5.3.1.3-1 starting from the edge of the assigned *NR* channel bandwidth. The spurious emission limits in Table 6.5.3.1.3-2 apply for all transmitter band configurations (NRB) and channel bandwidths. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

#### Table 6.5.3.1.3-1: Boundary between NR out of band and spurious emission domain

Channel bandwidth	50 MHz	100 MHz	200 MHz	400 MHz
OOB	100	200	400	800
boundary F <sub>оов</sub> (MHz)				

The spurious emission limits in table 6.5.3.1.3-2 apply for all transmitter band configurations (RB) and channel bandwidths.

Frequency Range	Maximum Level	Measurement bandwidth	NOTE
30 MHz ≤ f < 1000 MHz	-36 dBm	100 kHz	
1 GHz ≤ f < 12.75 GHz	-30 dBm	1 MHz	
12.75 GHz $\leq f \leq 2^{nd}$ harmonic of the upper frequency edge of the UL operating band in GHz	-13 dBm	1 MHz	

#### Table 6.5.3.1.3-2: Spurious emissions limits

The normative reference for this requirement is TS 38.101-2 subclause 6.5.3.

#### 6.5.3.1.4 Test description

#### 6.5.3.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

		Initial Conditions				
Test Enviro	Test Environment as specified in TS 38.508- Normal					
1 [10] subcl	ause 4.1					
	encies as specified in TS 38.508-	Low range, High range (NOTE 2)				
1 [10] subcl	ause 4.3.1					
	el Bandwidths as specified in TS	Highest				
	0] subclause 4.3.1					
Test SCS a	s specified in Table 5.3.5-1	120kHz				
		Test Parameters				
Test ID	Downlink Configuration	Uplink Configuration				
		Modulation	RB allocation			
			(NOTE 1)			
1	N/A for Spurious Emissions	DFT-s -OFDM QPSK	Inner_Full for PC2, PC3			
	testing		and PC4			
	looting		Inner_Full_Region1 for			
	_		PC1			
2		DFT-s -OFDM QPSK	Inner_1RB (NOTE 3)			
		RB allocation is defined in Table 6.1-1 for P	C2, PC3 and PC4 or Table			
6.1-2 for PC1.						
NOTE 2: When testing Low range test only in Frequency Range lower than ( $F_{UL_{IOW}} - \Delta f_{OOB}$ ) and when testing High						
	range test only in Frequency Range higher than ( $F_{UL\_high} + \Delta f_{OOB}$ ).					
		uplink RB to Inner_1RB_Left for PC2, PC3				
	Inner_1RB_Region1 for PC1 and when testing High range configure uplink RB to Inner_1RB_Right for					
l F	PC2, PC3 and PC4 or Inner_1RB_I					

#### Table 6.5.3.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.3.1.4.3.

#### 6.5.3.1.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</li>
- 3. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 4. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 5. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.

- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 7. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4). Step (a) is optional and applicable only if SNR (test requirement level in Table 6.5.3.1.5-1 minus offset value minus noise floor of the test system)  $\ge 0$  dB is guaranteed.
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex K, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.1.3-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.1.3-2 may be applied. The measurement period shall capture the active time slots. For each spurious emission frequency with coarse TRP identified to be less than an offset dB from the TRP limit according to Table 6.5.3.1.3-2, continue with fine TRP procedures according to step (b).

The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element, excluding the influence of noise. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.

Grid	Frequency Range	Offset Value		
Constant Density	6 GHz ≤ f < 12.75 GHz	5.13		
	12.75 GHz ≤ f ≤ 23.45GHz	5.09		
	23.45 GHz ≤ f ≤ 40.8GHz	5.38		
	40.8 GHz ≤ f ≤ 66GHz	7.31		
	66 GHz ≤ f ≤ 80GHz	[7.61]		
Constant-Step Size	6 GHz ≤ f < 12.75 GHz	5.26		
	12.75 GHz ≤ f ≤ 23.45GHz	5.23		
	23.45 GHz ≤ f ≤ 40.8GHz	5.52		
	40.8 GHz ≤ f ≤ 66GHz	7.43		
	66 GHz ≤ f ≤ 80GHz	[7.73]		
NOTE 1: These offset values a	are the upper limit values when fir	ne TRP measurement		
<ul> <li>uncertainty of the test system is same as maximum test system uncertainty in Annex F and when using the coarse measurement grid with minimum number of points as specified in Table M.4.5-3.</li> <li>NOTE 2: It is allowed to use the offset values derived based on test system's actual measurement uncertainty budget and denser measurement grid as specified in Table M.4.5.3.</li> </ul>				

#### Table 6.5.3.1.4.2-1: Typical offset values for coarse TRP measurement step 7(a)

- (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.1.3-2.
- 8. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 6.5.3.1.3-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.5.3.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

#### 6.5.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5.3.1.5 Test requirement

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions requirement with frequency range as indicated in Table 6.5.3.1.5-1.

The maximum EIRP or TRP power of spurious emission, measured using RMS detector, shall not exceed the described value in Table 6.5.3.1.5-1.

Unless otherwise stated, the spurious emission limits apply for the frequency ranges that are more than  $F_{OOB}$  (MHz) in Table 6.5.3.1.3-1 starting from the edge of the assigned *NR* channel bandwidth. The spurious emission limits in Table 6.5.3.1.5-1 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

Table 6.5.3.1.5-1: Spurious emissions test requirements	Table	6.5.3.1	.5-1: \$	Spurious	emissions	test red	quirements
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Frequency Range	Maximum Level	Measurement bandwidth	NOTE			
6 GHz ≤ f < 12.75 GHz	-30 dBm	1 MHz				
12.75 GHz $\leq f \leq 2^{nd}$ harmonic of the upper frequency edge of the UL operating band in GHz	-13 dBm	1 MHz				
NOTE 1: Applies for Band n257, n258, n260						

## 6.5.3.2 Spurious emission band UE co-existence

Editor's note: The following aspects are either missing or not yet determined:

#### - TRP Measurement uncertainty is TBD for PC1, PC2 and PC4.

#### 6.5.3.2.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

#### 6.5.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.5.3.2.3 Minimum conformance requirements

This clause specifies the requirements for the specified NR band, for co-existence with protected bands. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

The spurious emission UE co-existence limits in Table 6.5.3.2.3-1 apply for all transmitter band configurations (RB) and channel bandwidths.

	Spurious emission							
NR Band	Protected band/frequency range		ency MHz	range :)	Maximum Level (dBm)	MBW (MHz)	NOTE	
	NR Band n260	F <sub>DL_low</sub>	1	$F_{DL_high}$	-2	100		
n257	Frequency range	57000	-	66000	2	100		
	Frequency range	23600	1	24000	1	200	3	
n258	Frequency range	57000	1	66000	2	100		
n259	NR Band 257	FDL_low	-	$F_{DL_high}$	-5	100	n259	
	NR Band 261	$F_{DL\_low}$	-	$F_{DL_high}$	-5	100		
	Frequency range	36000	-	37000	7	1000		
	Frequency range	57000	-	66000	2	100		
	NR Band 257	$F_{DL_{low}}$	-	FDL_high	-5	100		
n260	NR Band 261	FDL_low	-	FDL_high	-5	100		
	Frequency range	57000	-	66000	2	100		
- 2001	NR Band 260	FDL_low	-	FDL_high	-2	100		
n261	Frequency range	57000	-	66000	2	100		
NOTE 1:	FDL_low and FDL_high refer to each NR freq	uency bar	nd sp	ecified in	Table 5.2-1.			
NOTE 2:		-	-					
NOTE 3:	The protection of frequency range 23600-24000 MHz is meant for protection of satellite passive							
	services.							

Table 6.5.3.2.3-1: Spurious emissions UE co-existence limits

The normative reference for this requirement is TS 38.101-2 subclause 6.5.3.1.

### 6.5.3.2.4 Test description

#### 6.5.3.2.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

#### Table 6.5.3.2.4.1-1: Test Configuration Table

	Initial Conditions					
Test Environment as specified in TS 38.508- Normal						
1 [10] subcla	1 [10] subclause 4.1					
Test Freque	Test Frequencies as specified in TS 38.508- Low range, High range (NOTE 2)					
1 [10] subcla	1 [10] subclause 4.3.1					
	el Bandwidths as specified in TS	Highest				
38.508-1 [10] subclause 4.3.1						
Test SCS as	s specified in Table 5.3.5-1	120kHz				
	1	Test Parameters				
Test ID	Downlink Configuration	Uplink Configuration				
		Modulation	RB allocation			
	_		(NOTE 1)			
1	N/A for Spurious Emissions	DFT-s-OFDM QPSK	Inner_Full for PC2, PC3			
	testing Inner_Full_Region1 for					
	4		PC1			
2		DFT-s-OFDM QPSK	Inner_1RB (NOTE 3)			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
6.1-2 for PC1.						
NOTE 2: When testing Low range test only in Frequency Range lower than ( $F_{UL_{IOW}} - \Delta f_{OOB}$ ) and when testing High						
range test only in Frequency Range higher than $(F_{UL\_high} + \Delta f_{OOB})$ .						
	NOTE 3: When testing Low range configure uplink RB to Inner_1RB_Left for PC2, PC3 and PC4 or					
Inner_1RB_Region1 for PC1 and when testing High range configure uplink RB to Inner_1RB_Right for						
PC2, PC3 and PC4 or Inner_1RB_Region1 for PC1.						

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.3.2.4.1-1
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.3.2.4.3.

#### 6.5.3.2.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</li>
- 3. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.5.3.2.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 4. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 5. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 7. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4):
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex K, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.2.3-1. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.2.3-1 may be applied as long as the SNR (ratio of test limit to floor noise of test equipment)  $\geq$  10dB is guaranteed. The measurement period shall capture the active time slots. For each spurious emission frequency with coarse TRP identified to be less than an offset dB (NOTE 2) from the TRP limit according to Table 6.5.3.2.3-1, continue with fine TRP procedures according to step (b).

The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.

- (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.2.3-1.
- 8. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.

- NOTE 1: The frequency range defined in Table 6.5.3.2.3-1 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: The coarse TRP measurement grid and corresponding offset dB value referred in step 5(a) above, for some valid grids can be found in TR 38.903 section B.18.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

#### 6.5.3.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5.3.2.5 Test requirement

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions for UE coexistence requirement with frequency range as indicated in Table 6.5.3.2.5-1.

The maximum EIRP or TRP power of spurious emission for UE co-existence, measured using RMS detector, shall not exceed the described value in Table 6.5.3.2.5-1.

The spurious emission UE co-existence limits in Table 6.5.3.2.5-1 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

	Spurious emission						
NR Band	Protected band/frequency range		ency MHz	range	Maximum Level	MBW (MHz)	NOTE
Dana		,		<i>.</i> /	(dBm)	(	
	NR Band n260	F <sub>DL_low</sub>	-	$F_{DL_high}$	-2 + 5.0	100	NOTE 3
n257	Frequency range	57000	-	66000	2	100	
	Frequency range	23600	-	24000	1 + TBD	200	
n258	Frequency range	57000	-	66000	2	100	
n259	NR Band 257	F <sub>DL_low</sub>	-	FDL_high	-5 + 3.3	100	n259,
							NOTE 4
	NR Band 261	$F_{DL\_low}$	-	$F_{DL_high}$	-5 + 3.3	100	NOTE 4
	Frequency range	36000	i	37000	7 + 6.0	1000	NOTE 5
	Frequency range	57000	-	66000	2	100	
	NR Band 257	$F_{DL\_low}$	i	$F_{DL_high}$	-5 + 3.3	100	NOTE 4
n260	NR Band 261	$F_{DL_{low}}$	-	$F_{DL_high}$	-5 + 3.3	100	NOTE 4
	Frequency range	57000	-	66000	2	100	
n261	NR Band 260	F <sub>DL_low</sub>	-	$F_{DL_high}$	-2 + 5.0	100	NOTE 3
11201	Frequency range	57000	-	66000	2	100	
NOTE 1:	F <sub>DL_low</sub> and F <sub>DL_high</sub> refer to each NR freq	uency bar	nd sp	ecified in	Table 5.2-1.		
NOTE 2:	Void.						
	5.0 dB relaxation due to testability limit						
	3.3 dB relaxation due to testability limit						
NOTE 5:	6.0 dB relaxation due to testability limit						

#### Table 6.5.3.2.5-1: Spurious emissions UE co-existence test requirements

## 6.5.3.3 Additional Spurious emission

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Testability issue for 6GHz ~ [12.75GHz] is identified. How to treat this frequency range is TBD.
- TRP Measurement uncertainty is TBD
- NS\_202 & NS\_203 TP analysis pending
- NS\_202 & NS\_203 message content is pending

#### 6.5.3.3.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5.3.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

#### 6.5.3.3.3 Minimum conformance requirements

The additional spurious emission limits in Table 6.5.3.3.3-1 and Table 6.5.3.3.3-2 apply for all transmitter band configurations (RB) and channel bandwidths. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

When "NS\_201" is indicated in the cell, the power of any UE emission shall not exceed the levels specified in Table 6.5.3.3.3-1. This requirement also applies for the frequency ranges that are less than  $F_{OOB}$  (MHz) in Table 6.5.3-1 from the edge of the channel bandwidth.

#### Table 6.5.3.3.3-1: Void

When "NS\_202" is indicated in the cell, the power of any UE emission shall not exceed the levels specified in Table 6.5.3.3.2-2.

Frequency Range	Maximum Level	Measurement bandwidth
7.25 GHz ≤ f ≤ 2 <sup>nd</sup> harmonic of the upper frequency edge of the UL operating band	-10 dBm	100 MHz
23.6 GHz ≤ f ≤ 24.0 GHz	+1 dBm	200 MHz
$\begin{array}{l} 23.6 \text{ GHz} \leq f \leq 24.0 \\ \text{GHz} \end{array}$	+1 dBm	200 MHz

Table 6.5.3.3.3-2: Additional spurious emissions (NS\_202) test limits

When "NS\_203" is indicated in the cell, the power of any UE emission shall not exceed the levels specified in Table 6.5.3.2.4-1. This requirement also applies for the frequency ranges that are less than  $F_{OOB}$  (MHz) in Table 6.5.3.2.3-1 from the edge of the channel bandwidth.

Frequency band (GHz)	Spectrum emission limit (dBm)	Measurement bandwidth
$23.6 \le f \le 24.0$	+1	200 MHz

Table 6.5.3.3.3-3: Additional spurious emissions	(NS_203) test limits
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The normative reference for this requirement is TS 38.101-2 subclause 6.5.3.2.

#### 6.5.3.3.4 Test description

#### 6.5.3.3.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

Initial Conditions					
	ment as specified in TS 38.508-	Normal			
1 [10] subcla	use 4.1				
	ncies as specified in TS 38.508-	Low range			
1 [10] subcla	use 4.3.1				
Test Channe	I Bandwidths as specified in TS	Highest			
	] subclause 4.3.1				
Test SCS as	specified in Table 5.3.5-1	120kHz			
		Test Parameters			
Test ID	Downlink Configuration	Uplink Configuration			
		Modulation	RB allocation		
			(NOTE 1)		
1		DFT-s-OFDM QPSK	Inner_Full for PC2, PC3		
			and PC4		
	N/A for Spurious Emissions		Inner_Full_Region1 for		
	testing		PC1		
2		DFT-s-OFDM QPSK	Inner_1RB_Left for PC2,		
			PC3 and PC4		
			Inner_1RB_Left_Region1		
			for PC1		
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table					
6.1-2 for PC1.					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5.3.3.4.1-1
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5.3.3.4.3.

#### 6.5.3.3.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- 2. If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range  $0^{\circ} \le \theta \le 90^{\circ}$  for the alignment option selected in step 1; position the device

in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range  $90^{\circ} < \theta \le 180^{\circ}$  for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.

- 3. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.5.3.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 4. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>.
- 5. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 7. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4):
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex K, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M.. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.1.3-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.1.3-2 may be applied as long as the SNR (ratio of test limit to floor noise of test equipment)  $\geq$  10dB is guaranteed. The measurement period shall capture the [active time slots]. For each spurious emission frequency with coarse TRP identified to be less than an offset dB (NOTE 2) from the TRP limit according to Table 6.5.3.1.3-2, continue with fine TRP procedures according to step (b).
  - The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.
  - (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.1.3-2.
- 8. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 6.5.3.1.3-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: The coarse TRP measurement grid and corresponding offset dB value referred in step 5(a) above, for some valid grids can be found in TR 38.903 section B.18.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test

#### 6.5.3.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5.3.3.5 Test requirement

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions for UE coexistence requirement with frequency range as indicated in Table 6.5.3.3.5-1, Table 6.5.3.3.5-2 and Table 6.5.3.3.5-3.

The maximum EIRP or TRP power of spurious emission for UE co-existence, measured using RMS detector, shall not exceed the described value in Table 6.5.3.3.5-1, Table 6.5.3.3.5-2 and Table 6.5.3.3.5-3.

The spurious emission UE co-existence limits in Table 6.5.3.3.5-1, Table 6.5.3.3.5-2 and Table 6.5.3.3.5-3 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

#### Table 6.5.3.3.5-1: Void

#### Table 6.5.3.3.5-2: Additional spurious emissions (NS\_202) test requirements

Frequency Range	Maximum Level	Measurement bandwidth
7.25 GHz $\leq$ f $\leq$ 2 <sup>nd</sup> harmonic of the upper frequency edge of the UL operating band	-10 dBm	100 MHz
23.6 GHz ≤ f ≤ 24.0 GHz	+1 dBm	200 MHz

#### Table 6.5.3.3.5-3: Additional spurious emissions (NS\_203) test requirements

Frequency band (GHz)	Spectrum emission limit (dBm)	Measurement bandwidth
$23.6 \le f \le 24.0$	+1	200 MHz

# 6.5A Output RF spectrum emissions for CA

## 6.5A.1 Occupied bandwidth for CA

#### 6.5A.1.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the occupied bandwidth is a measure of the bandwidth containing 99 % of the total integrated power of the transmitted spectrum. The occupied bandwidth for CA shall be less than the aggregated channel bandwidth defined in subclause 5.5A.

The occupied bandwidth for CA is defined as a directional requirement. The requirement is verified in beam locked mode on beam peak direction.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5A.1.

## 6.5A.1.1 Occupied bandwidth for CA (2UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

## 6.5A.1.1.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

## 6.5A.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

## 6.5A.1.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

## 6.5A.1.1.4 Test description

## 6.5A.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR CA configuration specified in Table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA combination and subcarrier spacing, are shown in table 6.5A.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 6.5A.1.1.4.1-1: Test Configuration Table

Default Conditions							
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Mid range				
5.5A.1 Config	Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Highest aggregated BW of the CA configuration				
Test SCS as specified in Table 5.3.5-1.			Lowest				
	Test Parameters						
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)	
1	PCC	Default	Default	N/A	CP-OFDM QPSK	Outer_Full	
	SCC	Deiault	Delault	N/A	CP-OFDM QPSK	Outer_Full	
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.							

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1, C.2 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement Channel is set according to Table 6.5A.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.

6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.1.1.4.3.

6.5A.1.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2, and C.3.0 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.1.1.4.3
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.2).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5A.1.1.4.1-1 on both PCC and SCC(s). Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. Measure the EIRP spectrum distribution over all component carriers within two times or more frequency range over the requirement for Occupied Bandwidth for CA specification centring on the current carrier frequency. The characteristics of the filter shall be approximately Gaussian (typical spectrum analyser filter). The measuring duration is one active uplink subframe. EIRP is captured from both polarizations, theta and phi.
- 8. Calculate the total EIRP from both polarizations, theta and phi, within the range of all frequencies measured in step 4 and save this value as "Total EIRP". EIRP measurement procedure is defined in Annex K.
- 9. Identify the measurement window whose centre is aligned on the centre of the channel for which the sum of the power measured in theta and phi polarization is 99% of the "Total EIRP".
- 10. The "Occupied Bandwidth" is the width of the measurement window obtained in step 9.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.5A.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5A.1.1.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

## 6.5A.1.2 Occupied bandwidth for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

#### 6.5A.1.2.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

#### 6.5A.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.5A.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

#### 6.5A.1.2.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

#### - Instead of Table 6.5A.1.1.4.1-1 $\rightarrow$ use Table 6.5A.1.2.4.1-1.

#### Table 6.5A.1.2.4.1-1: Test Configuration Table

	Default Conditions					
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal			
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.			Mid range			
Test CC combination setting as specified in subclause 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2 for the CA Configuration across bandwidth combination sets supported by the UE.		Highest aggregated BW of the CA configuration				
Test S	Test SCS as specified in Table 5.3.5-1.			Lowest		
	Test Parameters					
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
	PCC				CP-OFDM QPSK	Outer_Full
1	SCC1	Default	Default	N/A	CP-OFDM QPSK	Outer_Full
	SCC2				CP-OFDM QPSK	Outer_Full
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

## 6.5A.1.2.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

## 6.5A.1.3 Occupied bandwidth for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

#### 6.5A.1.3.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

#### 6.5A.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.5A.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

#### 6.5A.1.3.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

- Instead of Table 6.5A.1.1.4.1-1 → use Table 6.5A.1.3.4.1-1.

Default Conditions							
Test E	nvironment as	s specified in TS	38.508-1 [10]	Normal			
subcla	subclause 4.1						
		specified in TS		Mid range			
	•	-	bandwidth classes,				
		are mapped ont					
		ng to Table 6.1-2					
			ified in subclause	Highest aggreg	ated BW of the CA co	onfiguration	
			he CA Configuration				
-			supported by the UE.				
Test S	CS as specifie	ed in Table 5.3.5		Lowest			
			Test Par	ameters			
Test	СС	ChBw(MHz)	Test frequency	DL RB	UL Modulation	UL RB allocation	
ID	00		rest requertey	allocation		(Note 1)	
	PCC				CP-OFDM QPSK	Outer_Full	
4	SCC1	Default	Default	N/A	CP-OFDM QPSK	Outer_Full	
I	SCC2	Delault	Delault	IN/A	CP-OFDM QPSK	Outer_Full	
SCC3					CP-OFDM QPSK	Outer_Full	
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
	6.1-2 for PC1.						

# Table 6.5A.1.3.4.1-1: Test Configuration Table

## 6.5A.1.3.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

# 6.5A.1.4 Occupied bandwidth for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

## 6.5A.1.4.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

## 6.5A.1.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

## 6.5A.1.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

6.5A.1.4.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

- Instead of Table 6.5A.1.1.4.1-1  $\rightarrow$  use Table 6.5A.1.4.4.1-1.

	Default Conditions						
Test E	nvironment as	s specified in TS	38.508-1 [10]	Normal			
subcla	subclause 4.1						
		s specified in TS		Mid range			
	•	-	bandwidth classes,				
		are mapped on					
-		ng to Table 6.1-2					
			cified in subclause	Highest aggreg	ated BW of the CA co	onfiguration	
			he CA Configuration				
			supported by the UE.				
Test S	CS as specifie	ed in Table 5.3.5		Lowest			
	1	r	Test Par		1		
Test	CC	ChBw(MHz)	Test frequency	DL RB	UL Modulation	UL RB allocation	
ID		02(		allocation		(Note 1)	
	PCC				CP-OFDM QPSK	Outer_Full	
	SCC1				CP-OFDM QPSK	Outer_Full	
1	SCC2	Default	Default	N/A	CP-OFDM QPSK	Outer_Full	
	SCC3				CP-OFDM QPSK	Outer_Full	
	SCC4 CP-OFDM QPSK Outer_Full						
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
	6.1-2 for I	PC1.					

## Table 6.5A.1.4.4.1-1: Test Configuration Table

#### 6.5A.1.4.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

## 6.5A.1.5 Occupied bandwidth for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

## 6.5A.1.5.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

#### 6.5A.1.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.5A.1.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

#### 6.5A.1.5.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

- Instead of Table 6.5A.1.1.4.1-1 $\rightarrow$  use Table 6.5A.1.5.4.1-1.

Default Conditions						
	Test Environment as specified in TS 38.508-1 [10]			Normal		
	subclause 4.1					
		s specified in TS		Mid range		
			bandwidth classes,			
		are mapped ont				
		ng to Table 6.1-2				<i>4</i>
			ified in subclause	Highest aggree	pated BW of the CA co	onfiguration
			he CA Configuration			
	across bandwidth combination sets supported by the UE. Test SCS as specified in Table 5.3.5-1.					
Test S	CS as specing		Test Par	Lowest		
Test			iest rai	DL RB		UL RB allocation
ID	CC	ChBw(MHz)	Test frequency	allocation	UL Modulation	(Note 1)
	PCC				CP-OFDM QPSK	Outer_Full
	SCC1				CP-OFDM QPSK	Outer_Full
1	SCC2	Default	Default	N/A	CP-OFDM QPSK	Outer_Full
1	SCC3	SCC3 Default Default		IN/A	CP-OFDM QPSK	Outer_Full
	SCC4				CP-OFDM QPSK	Outer_Full
	SCC5			CP-OFDM QPSK	Outer_Full	
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.					

## Table 6.5A.1.5.4.1-1: Test Configuration Table

## 6.5A.1.5.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

## 6.5A.1.6 Occupied bandwidth for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

## 6.5A.1.6.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

#### 6.5A.1.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.5A.1.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

## 6.5A.1.6.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

- Instead of Table 6.5A.1.1.4.1-1 → use Table 6.5A.1.6.4.1-1.

Default Conditions							
		s specified in TS	38.508-1 [10]	Normal			
	use 4.1						
		specified in TS		Mid range			
			bandwidth classes,				
		are mapped ont					
		ng to Table 6.1-2					
			ified in subclause	Highest aggreg	ated BW of the CA co	onfiguration	
			he CA Configuration				
			supported by the UE.				
Test S	CS as specifie	ed in Table 5.3.5		Lowest			
		,,	Test Para	ameters			
Test	СС	ChBw(MHz)	Test frequency	DL RB	UL Modulation	UL RB allocation	
ID			restricqueriey	allocation		(Note 1)	
	PCC				CP-OFDM QPSK	Outer_Full	
	SCC1				CP-OFDM QPSK	Outer_Full	
	SCC2				CP-OFDM QPSK	Outer_Full	
1	SCC3	Default	Default	N/A	CP-OFDM QPSK	Outer_Full	
	SCC4				CP-OFDM QPSK	Outer_Full	
	SCC5				CP-OFDM QPSK	Outer_Full	
SCC6 CP-OFDM QPS						Outer_Full	
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
	6.1-2 for I	PC1.					

## Table 6.5A.1.6.4.1-1: Test Configuration Table

## 6.5A.1.6.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

## 6.5A.1.7 Occupied bandwidth for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD

## 6.5A.1.7.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE are less than their specific limits.

## 6.5A.1.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

## 6.5A.1.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.1.0.

## 6.5A.1.7.4 Test description

Same as in clause 6.5A.1.1.4 with following exceptions:

- Instead of Table 6.5A.1.1.4.1-1 $\rightarrow$  use Table 6.5A.1.7.4.1-1.

Default Conditions							
Test E	nvironment as	s specified in TS	38.508-1 [10]	Normal			
subcla	use 4.1						
		s specified in TS		Mid range			
			bandwidth classes,				
		are mapped ont					
		ng to Table 6.1-2					
			cified in subclause	Highest aggreg	ated BW of the CA co	onfiguration	
			he CA Configuration				
			supported by the UE.				
Test S	CS as specifie	ed in Table 5.3.5		Lowest			
			Test Par	ameters			
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)	
	PCC				CP-OFDM QPSK	Outer_Full	
	SCC1				CP-OFDM QPSK	Outer_Full	
	SCC2				CP-OFDM QPSK	Outer_Full	
1	SCC3	Default	Default	N/A	CP-OFDM QPSK	Outer_Full	
1	SCC4	Delault	Delault	IN/A	CP-OFDM QPSK	Outer_Full	
	SCC5				CP-OFDM QPSK	Outer_Full	
	SCC6				CP-OFDM QPSK	Outer_Full	
	SCC7 CP-OFDM QPSK Outer_Full						
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.						

## Table 6.5A.1.7.4.1-1: Test Configuration Table

## 6.5A.1.7.5 Test requirement

The measured Occupied Bandwidth shall not exceed the aggregated channel bandwidth defined in subclause 5.5A.

# 6.5A.2 Out of band emission for CA

## 6.5A.2.1 Spectrum Emission Mask for CA

## 6.5A.2.1.0 Minimum conformance requirements

The requirement specified in this section shall apply if the UE has at least one of UL or DL configured for CA or if the UE is configured for single CC operation with different channel bandwidths in UL and DL carriers.

For intra-band contiguous carrier aggregation, the spectrum emission mask of the UE applies to frequencies ( $\Delta f_{OOB}$ ) starting from the ± edge of the aggregated channel bandwidth (Table 5.3A.5-1). For any bandwidth class defined in Table 5.3A.5-1, the UE emission shall not exceed the levels specified in Table 6.5A.2.1.0-1. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

# Table 6.5A.2.1.0-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth				
$\pm$ 0-0.1*BW <sub>Channel_CA</sub>	-5	1 MHz				
$\pm 0.1^{*}BW_{Channel_CA}$ -	-13	1 MHz				
2*BW <sub>Channel_CA</sub>						
	NOTE 1: If carrier leakage or I/Q image lands inside the spectrum occupied by the					
configured UL and DL CCs, exception to the general spectrum emission mask limit						
applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall						
apply. For I/Q image th	e requirements specified in section	n 6.4A.2.3.0 shall apply.				

## 6.5A.2.1.1 Spectrum Emission Mask for CA (2UL CA)

Editor's note: The following aspects are either missing or not yet determined:

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- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4

## 6.5A.2.1.1.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

## 6.5A.2.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

# 6.5A.2.1.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

- 6.5A.2.1.1.4 Test description
- 6.5A.2.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR CA configurations specified in table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA combination and subcarrier spacing, are shown in table 6.5A.2.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Default Conditions							
		s specified in TS 38.	508-1 [10]	Normal			
Test Fr subclar classes	subclause 4.1 Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.		Mid range				
Test C 5.5A.1- Configu suppor	C combination -1, 5.5A.2-1 a uration across ted by the UE	n setting as specifie nd 5.5A.2-2 for the s bandwidth combin	CA	Highest aggrega	ated BW of the CA cor	nfiguration	
Test S	CS as specifie	ed in Table 5.3.5-1.	Tost Pa	Lowest, Highest rameters	t		
Test ID	CC	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)	
	PCC				DFT-s-OFDM PI/2 BPSK	Outer_1RB_Left	
1	SCCs				DFT-s-OFDM PI/2 BPSK	Outer_1RB_Left	
2	PCC				DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right	
	SCCs				DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right	
3	PCC				DFT-s-OFDM PI/2 BPSK	Outer_Full	
	SCCs				DFT-s-OFDM PI/2 BPSK	Outer_Full	
4	PCC				DFT-s-OFDM QPSK	Outer_1RB_Left	
-	SCCs				DFT-s-OFDM QPSK	Outer_1RB_Left	
5	PCC				DFT-s-OFDM QPSK	Outer_1RB_Right	
Ŭ	SCCs				DFT-s-OFDM QPSK	Outer_1RB_Right	
6	PCC				DFT-s-OFDM QPSK	Outer_Full	
	SCCs				DFT-s-OFDM QPSK	Outer_Full	
7	PCC	Default	Default	N/A	DFT-s-OFDM 16QAM	Outer_1RB_Left	
	SCCs				DFT-s-OFDM 16QAM	Outer_1RB_Left	
8	PCC				DFT-s-OFDM 16QAM	Outer_1RB_Right	
	SCCs				DFT-s-OFDM 16QAM	Outer_1RB_Right	
9	PCC				DFT-s-OFDM 16QAM	Outer_Full	
Ŭ	SCCs				DFT-s-OFDM 16QAM	Outer_Full	
10	PCC				DFT-s-OFDM 64QAM	Outer_1RB_Left	
	SCCs				DFT-s-OFDM 64QAM	Outer_1RB_Left	
11	PCC				DFT-s-OFDM 64QAM	Outer_1RB_Right	
	SCCs				DFT-s-OFDM 64QAM	Outer_1RB_Right	
12	PCC				DFT-s-OFDM 64QAM	Outer_Full	
	SCCs				DFT-s-OFDM 64QAM	Outer_Full	
13	PCC SCCs				CP-OFDM QPSK CP-OFDM QPSK	Outer_1RB_Left Outer_1RB_Left	

# Table 6.5A.2.1.1.4.1-1: Test Configuration Table

14	PCC				CP-OFDM QPSK	Outer_1RB_Right
14	SCCs				CP-OFDM QPSK	Outer_1RB_Right
15	PCC				CP-OFDM QPSK	Outer_Full
15	SCCs				CP-OFDM QPSK	Outer_Full
NOTE	NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1, C.2 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5A.2.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.2.1.1.4.3

6.5A.2.1.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2, and C.3 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.2.1.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5A.2.1.1.4.1-1 on both PCC and SCC(s). Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. Measure the TRP of the transmitted signal with a measurement filter of bandwidths according to table 6.5A.2.1.1.5-1. The centre frequency of the filter shall be stepped in continuous steps according to the same table. TRP shall be recorded for each step. The measurement period shall capture the active time slots. Total radiated power is measured according to TRP measurement procedure defined in Annex K. The measurement grid used for TRP measurement defined in Annex M. TRP is calculated considering both polarizations, theta and phi.
- NOTE 1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.5A.2.1.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.5A.2.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5A.2.1.1.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.1.5-1.

# Table 6.5A.2.1.1.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth		
± 0-0	0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz		
± 0.1	1*BWChannel_CA -	-13 + TT	1 MHz		
2	*BWChannel_CA				
NOTE 2:	<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.1.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>				
	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.				
NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth.					

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.2 Spectrum Emission Mask for CA (3UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD.

## 6.5A.2.1.2.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.5A.2.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

## 6.5A.2.1.2.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1→ use Table 6.5A.2.1.2.5-1.

## 6.5A.2.1.2.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.2.5-1.

# Table 6.5A.2.1.2.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth		
± 0-	-0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz		
± 0	.1*BW <sub>Channel_CA</sub> -	-13 + TT	1 MHz		
	2*BWChannel_CA				
NOTE 2:	<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.2.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>				
NOTE 3:	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement positio with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.				
NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth					

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.3 Spectrum Emission Mask for CA (4UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD.

## 6.5A.2.1.3.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.5A.2.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

## 6.5A.2.1.3.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1  $\rightarrow$  use Table 6.5A.2.1.3.5-1.

## 6.5A.2.1.3.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.3.5-1.

# Table 6.5A.2.1.3.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth
± 0-0	.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz
± 0.1	*BWChannel_CA -	-13 + TT	1 MHz
2*	BW <sub>Channel_CA</sub>		
NOTE 2: I	<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.3.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>		
	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.		
0	NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth		

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.4 Spectrum Emission Mask for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD.

## 6.5A.2.1.4.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

#### 6.5A.2.1.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

#### 6.5A.2.1.4.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1→ use Table 6.5A.2.1.4.5-1.

## 6.5A.2.1.4.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.4.5-1.

# Table 6.5A.2.1.4.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

Δf <sub>00B</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth
$\pm$ 0-0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz
$\pm0.1^{*}\mathrm{BW}_{\mathrm{Channel}_{CA}}$ -	-13 + TT	1 MHz
2*BWChannel_CA		
<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.4.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>		
NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.		
NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth		

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.5 Spectrum Emission Mask for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA TBD.

## 6.5A.2.1.5.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.5A.2.1.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

## 6.5A.2.1.5.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1→ use Table 6.5A.2.1.5.5-1.

## 6.5A.2.1.5.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.5.5-1.

# Table 6.5A.2.1.5.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth
± 0-0	0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz
± 0.	1*BWChannel_CA -	-13 + TT	1 MHz
2	*BWChannel_CA		
NOTE 2:	<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.5.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>		
NOTE 3:	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.		
NOTE 4:	NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth		

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.6 Spectrum Emission Mask for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD.

## 6.5A.2.1.6.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

#### 6.5A.2.1.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

#### 6.5A.2.1.6.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1→ use Table 6.5A.2.1.6.5-1.

#### 6.5A.2.1.6.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.6.5-1.

# Table 6.5A.2.1.6.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth
± 0·	-0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz
± 0	.1*BWChannel_CA -	-13 + TT	1 MHz
2	2*BWChannel_CA		
<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.6.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>			
NOTE 3:	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.		
NOTE 4:	NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth		

Table 6.5A.2.1.6.5-1a: Test Tolerance (Aggregated BW ≤ 40	00MHz)
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Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

## 6.5A.2.1.7 Spectrum Emission Mask for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz and for intra-band non-contiguous CA are TBD.

## 6.5A.2.1.7.1 Test purpose

To verify that the power of any UE emission shall not exceed specified levels for the specified channel bandwidth for CA.

#### 6.5A.2.1.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

#### 6.5A.2.1.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.1.0.

#### 6.5A.2.1.7.4 Test description

Same as in clause 6.5A.2.1.1.4 with following exceptions:

- Instead of Table 6.5A.2.1.1.5-1→ use Table 6.5A.2.1.7.5-1.

## 6.5A.2.1.7.5 Test Requirements

The measured TRP of any UE emission derived in step 7, shall fulfil requirements in Table.6.5A.2.1.7.5-1.

# Table 6.5A.2.1.7.5-1: General NR spectrum emission mask for intra-band contiguous CA in frequency range 2

	Δf <sub>оов</sub> (MHz)	Any carrier aggregation bandwidth class	Measurement bandwidth	
± 0·	-0.1*BW <sub>Channel_CA</sub>	-5 + TT	1 MHz	
± 0	.1*BWChannel_CA -	-13 + TT	1 MHz	
2	2*BWChannel_CA			
<ul> <li>NOTE 1: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.1.7.5-1a</li> <li>NOTE 2: If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the general spectrum emission mask limit applies. For carrier leakage the requirements specified in section 6.4A.2.2.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.</li> </ul>				
NOTE 3:	NOTE 3: At the boundary of spectrum emission limit, the first and last measurement position with a 1 MHz filter is the inside of +0.5MHz and -0.5MHz, respectively.			
NOTE 4:	NOTE 4: The measurements are to be performed above the upper edge of the aggregated channel bandwidth and below the lower edge of the aggregated channel bandwidth			

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	3.21 dB	3.46 dB

# 6.5A.2.2 Adjacent channel leakage ratio for CA

## 6.5A.2.2.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the carrier aggregation NR adjacent channel leakage power ratio (CA  $NR_{ACLR}$ ) is the ratio of the filtered mean power centred on the aggregated channel bandwidth to the filtered mean power centred on an adjacent aggregated channel bandwidth at spacing equal to the aggregated channel bandwidth. The assigned aggregated channel bandwidth power and adjacent aggregated channel bandwidth power are measured with rectangular filters with measurement bandwidths specified in 6.5A.2.2.0-1. If the measured adjacent channel power is greater than -35 dBm then the  $NR_{ACLR}$  shall be higher than the value specified in Table 6.5A.2.2.0-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth
	Any CA bandwidth class
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 dB
CA NR <sub>ACLR</sub> for band n260	16 dB
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel_{CA}} - 2*BW_{GB}$
Adjacent channel centre frequency offset (in MHz)	+ BW <sub>Channel_CA</sub>
NOTE 1: BW <sub>GB</sub> is defined in clause 5.3A.2.	- BWChannel_CA

## Table 6.5A.2.2.0-1: General requirements for CA NR<sub>ACLR</sub>

## 6.5A.2.2.1 Adjacent channel leakage ratio for CA (2UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances and Test limit analysis for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances and Test limit analysis are FFS for power class 1, 2 and 4.

## 6.5A.2.2.1.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

# 6.5A.2.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

## 6.5A.2.2.1.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

- 6.5A.2.2.1.4 Test description
- 6.5A.2.2.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR CA configurations specified in table 5.5A.1-1, 5.5A.2-1 and 5.5A.2-2. All of these configurations shall be tested with applicable test parameters for each CA combination and subcarrier spacing, are shown in table 6.5A.2.2.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

				Conditions		
Test Er subclau		s specified in TS 38	.508-1 [10]	Normal		
Test Frequencies as specified in TS 38.508-1 [10] subclause [4.3.1.2.3] for different CA bandwidth classes, and PCC and SCCs are mapped onto physical frequencies according to Table 6.1-2.		Low and High range				
Test Co 5.5A.1- Configu suppor	C combinatior -1, 5.5A.2-1 a uration across ted by the UE	n setting as specifie nd 5.5A.2-2 for the bandwidth combin	CA ation sets		ated BW of the CA cor	nfiguration
Test S	CS as specifie	ed in Table 5.3.5-1.		Lowest, Highest rameters	[	
Test ID	СС	ChBw(MHz)	Test frequency	DL RB allocation	UL Modulation	UL RB allocation (Note 1)
1	PCC		Low		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Left
	SCCs		Low		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Left
2	PCC		High		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right
۷	SCCs		High		DFT-s-OFDM PI/2 BPSK	Outer_1RB_Right
3	PCC		Default		DFT-s-OFDM PI/2 BPSK	Outer_Full
0	SCCs		Default		DFT-s-OFDM PI/2 BPSK	Outer_Full
4	PCC		Low		DFT-s-OFDM QPSK	Outer_1RB_Left
	SCCs	Low High High	Low		DFT-s-OFDM QPSK	Outer_1RB_Left
5	PCC		High		DFT-s-OFDM QPSK	Outer_1RB_Right
0	SCCs		High		DFT-s-OFDM QPSK	Outer_1RB_Right
6	PCC		Default		DFT-s-OFDM QPSK	Outer_Full
0	SCCs	Default	Default	N/A	DFT-s-OFDM QPSK	Outer_Full
7	PCC		Low		DFT-s-OFDM 16QAM	Outer_1RB_Left
,	SCCs		Low		DFT-s-OFDM 16QAM	Outer_1RB_Left
8	PCC		High		DFT-s-OFDM 16QAM	Outer_1RB_Right
U	SCCs		High		DFT-s-OFDM 16QAM	Outer_1RB_Right
9	PCC		Default		DFT-s-OFDM 16QAM	Outer_Full
0	SCCs		Default		DFT-s-OFDM 16QAM	Outer_Full
10	PCC		Default		DFT-s-OFDM 64QAM	Outer_Full
10	SCCs		Default		DFT-s-OFDM 64QAM	Outer_Full
11	PCC SCCs		Low Low		CP-OFDM QPSK CP-OFDM QPSK	Outer_1RB_Left Outer_1RB_Left
12	PCC		High High		CP-OFDM QPSK	Outer_1RB_Right
	SCCs PCC		High Default	1	CP-OFDM QPSK CP-OFDM QPSK	Outer_1RB_Right Outer_Full
13	SCCs		Default		CP-OFDM QPSK	Outer_Full
<ul> <li>NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.</li> <li>NOTE 2: Following Test IDs shall be skipped for FR2b         <ul> <li>All Test IDs for 400MHz and 200MHz aggregated Channel Bandwidth</li> </ul> </li> </ul>						

# Table 6.5A.2.2.1.4.1-1: Test Configuration Table

Test ID 1-2, 4-5, 7-12 for 100MHz aggregated Channel Bandwidth

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1, C.2 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5A.2.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.2.2.1.4.3

#### 6.5A.2.2.1.4.2 Test procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2, and C.3 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.2.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 4. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5A.2.2.1.4.1-1 on both PCC and SCC(s). Since the UE has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 5. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 7. Measure EIRP of the transmitted signal for the assigned NR channel with a rectangular measurement filter with bandwidths according to Table 6.5A.2.2.1.5-1. EIRP measurement procedure defined in Annex K. EIRP is calculated considering both polarizations, theta and phi.
- 8. Measure EIRP of the first NR adjacent channel on both lower and upper side of the assigned NR channel, respectively using a rectangular measurement filter with bandwidths according to Table 6.5A.2.2.1.5-1. EIRP measurement procedure defined in Annex K. EIRP is calculated considering both polarizations, theta and phi.
- 9. Calculate the ratios of the power between the values measured in step 7 over step 8 for lower and upper  $NR_{ACLR}$ , respectively.
- NOTE 1: When switching to DFT-s-OFDM waveform, as specified in the test configuration table 6.5A.2.2.1.4.1-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.

#### 6.5A.2.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

## 6.5A.2.2.1.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured  $NR_{ACLR}$ , derived in step 9, shall be higher than the limits in table 6.5A.2.2.1.5-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 - TT- R dB	
CA NR <sub>ACLR</sub> for band n260	16 - TT dB	
NR channel measurement bandwidth <sup>1</sup>	BW <sub>Channel_CA</sub> – 2*BW <sub>GB</sub>	
Adjacent channel centre frequency offset (in MHz)	+ BW <sub>Channel_CA</sub> / - BW <sub>Channel_CA</sub>	
<ul> <li>NOTE 1: BW<sub>GB</sub> is defined in clause 5.3A.2.</li> <li>NOTE 2: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.2.1.5-1a</li> <li>NOTE 3: R for each frequency, channel bandwidth and test point is specified in Table 6.5A.2.2.1.5-1b</li> </ul>		

Table 6.5A.2.2.1.5-1: General requirements for CA NR<sub>ACLR</sub>

Test Metric	Any CA bandwidth class	23.45GHz ≤ f ≤ 30.3GHz	30.3GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)			
	100 MHz	4.96 dB	4.96 dB
	200 MHz	4.96 dB	4.96 dB
	400 MHz	4.96 dB	4.96 dB

#### Table 6.5A.2.2.1.5-1b: Relaxation due to testability limit (Aggregated BW ≤ 400MHz)

			nel bandwidth / asurement band	
	Test ID	100 MHz	200 MHz	400 MHz
NR <sub>ACLR</sub> for band n257, n258, n261	1	0	3	6
	2	0	3	6
	3	0	0	3
	4	0	3	6
	5	0	3	6
	6	0	0	3
	7	0	3	6
	8	0	3	6
	9	0	2.5	5.5
	10	2	5	8
	11	0	3	6
	12	0	3	6
	13	0	0	3

## 6.5A.2.2.2 Adjacent channel leakage ratio for CA (3UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

## 6.5A.2.2.2.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

# 6.5A.2.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

## 6.5A.2.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

# 6.5A.2.2.2.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.2.5-1.

# 6.5A.2.2.2.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.5-1.

# Table 6.5A.2.2.2.5-1: General requirements for CA $\ensuremath{\mathsf{NR}_{\mathsf{ACLR}}}$

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 - TT - R dB	
CA NR <sub>ACLR</sub> for band n260	16 - TT dB	
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel_CA} - 2^*BW_{GB}$	
Adjacent channel centre frequency offset (in MHz)	+ BWChannel_CA / - BWChannel_CA	
<ul> <li>NOTE 1: BW<sub>GB</sub> is defined in clause 5.3A.2.</li> <li>NOTE 2: TT for each frequency and channel bandwidth is specified in Table 6.5A.2.2.5-1a</li> <li>NOTE 3: R for each frequency, channel bandwidth and test point is specified in Table 6.5A.2.2.1.5-1b</li> </ul>		

Table 6.5A.2.2.2.5-1a: Test Tolerance (Aggregated BW ≤ 400MHz)

Test Metric	Any CA bandwidth class	23.45GHz ≤ f ≤ 30.3GHz	30.3GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)			
	100 MHz	4.96 dB	4.96 dB
	200 MHz	4.96 dB	4.96 dB
	400 MHz	4.96 dB	4.96 dB

# 6.5A.2.2.3 Adjacent channel leakage ratio for CA (4UL CA)

Editor's note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances for intra-band contiguous CA supporting aggregated BW > 400MHz is TBD.
- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.

# 6.5A.2.2.3.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

# 6.5A.2.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

## 6.5A.2.2.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

#### 6.5A.2.2.3.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.3.5-1.

#### 6.5A.2.2.3.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.3.5-1.

## Table 6.5A.2.2.3.5-1: General requirements for CA NR<sub>ACLR</sub>

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 - TT - R dB	
CA NR <sub>ACLR</sub> for band n260	16 - TT dB	
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel_CA} - 2^*BW_{GB}$	
Adjacent channel centre frequency offset (in MHz)	+ BW <sub>Channel_CA</sub> / - BW <sub>Channel_CA</sub>	
NOTE 1:BW <sub>GB</sub> is defined in clause 5.3A.2.NOTE 2:TT for each frequency and channel barNOTE 3:R for each frequency, channel bandwid6.5A.2.2.1.5-1b	ndwidth is specified in Table 6.5A.2.2.3.5-1a	

Test Metric	Any CA bandwidth class	23.45GHz ≤ f ≤ 30.3GHz	30.3GHz < f ≤ 40.8GHz
IFF (Quiet Zone size ≤ 30 cm)			
	100 MHz	4.96 dB	4.96 dB
	200 MHz	4.96 dB	4.96 dB
	400 MHz	4.96 dB	4.96 dB

## 6.5A.2.2.4 Adjacent channel leakage ratio for CA (5UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are TBD.

#### 6.5A.2.2.4.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

#### 6.5A.2.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

#### 6.5A.2.2.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

# 6.5A.2.2.4.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.4.5-1.

## 6.5A.2.2.4.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.4.5-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth
	Any CA bandwidth class
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 – TT dB
CA NR <sub>ACLR</sub> for band n260	16 – TT dB
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel_CA} - 2^*BW_{GB}$
Adjacent channel centre frequency offset (in MHz)	+ BW <sub>Channel_CA</sub> / - BW <sub>Channel_CA</sub>
NOTE 1: BW <sub>GB</sub> is defined in clause 5.3A.2.	
NOTE 2: TT for each frequency and channel band	width is specified in Table 6.5A.2.2.4.5-1a

# Table 6.5A.2.2.4.5-1a: Test Tolerance (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[4.6] dB	[5.0] dB

# 6.5A.2.2.5 Adjacent channel leakage ratio for CA (6UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are TBD.

# 6.5A.2.2.5.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

# 6.5A.2.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

# 6.5A.2.2.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

# 6.5A.2.2.5.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.5.5-1.

# 6.5A.2.2.5.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.5.5-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 – TT dB	
CA NR <sub>ACLR</sub> for band n260	16 – TT dB	
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel}CA - 2*BW_{GB}$	
Adjacent channel centre frequency offset (in MHz)		
NOTE 1: BW <sub>GB</sub> is defined in clause 5.3A.2. NOTE 2: TT for each frequency and channel band		

## Table 6.5A.2.2.5.5-1: General requirements for CA NR<sub>ACLR</sub>

Table 6.5A.2.2.5.5-1a: Test Tolerance (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[4.6] dB	[5.0] dB

## 6.5A.2.2.6 Adjacent channel leakage ratio for CA (7UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are TBD.

## 6.5A.2.2.6.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

## 6.5A.2.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

## 6.5A.2.2.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

## 6.5A.2.2.6.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.6.5-1.

## 6.5A.2.2.6.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.6.5-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 – TT dB	
CA NR <sub>ACLR</sub> for band n260	16 – TT dB	
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel_CA} - 2^*BW_{GB}$	
Adjacent channel centre frequency offset (in MHz)	equency offset (in + BW <sub>Channel_CA</sub> // / - BW <sub>Channel_CA</sub>	
NOTE 1: BW <sub>GB</sub> is defined in clause 5.3A.2. NOTE 2: TT for each frequency and channel band		

## Table 6.5A.2.2.6.5-1: General requirements for CA NR<sub>ACLR</sub>

Table 6.5A.2.2.6.5-1a: Test Tolerance (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[4.6] dB	[5.0] dB

## 6.5A.2.2.7 Adjacent channel leakage ratio for CA (8UL CA)

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are TBD.

## 6.5A.2.2.7.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to adjacent channels in terms of Adjacent Channel Leakage power Ratio (ACLR) for CA.

## 6.5A.2.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

## 6.5A.2.2.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.2.2.0.

## 6.5A.2.2.7.4 Test description

Same as in clause 6.5A.2.2.1.4 with following exceptions:

- Instead of Table 6.5A.2.2.1.5-1  $\rightarrow$  use Table 6.5A.2.2.7.5-1.

## 6.5A.2.2.7.5 Test Requirements

If the measured adjacent channel power, derived in step 8, is greater than -35 dBm then the measured NR ACLR, derived in step 9, shall be higher than the limits in table 6.5A.2.2.7.5-1.

	CA bandwidth class / CA NR <sub>ACLR</sub> / Measurement bandwidth	
	Any CA bandwidth class	
CA NR <sub>ACLR</sub> for band n257, n258, n261	17 – TT dB	
CA NR <sub>ACLR</sub> for band n260	16 – TT dB	
NR channel measurement bandwidth <sup>1</sup>	$BW_{Channel}CA - 2*BW_{GB}$	
Adjacent channel centre frequency offset (in MHz)	ffset (in + BW <sub>Channel_CA</sub> / / - BW <sub>Channel_CA</sub>	
NOTE 1: BW <sub>GB</sub> is defined in clause 5.3A.2. NOTE 2: TT for each frequency and channel band		

Table 6.5A.2.2.7.5-1: General requirements for CA NR<sub>ACLR</sub>

Table 6.5A.2.2.7.5-1a: Test Tolerance (Aggregated BW ≤ 400MHz)

Test Metric	FR2a	FR2b
IFF (Quiet Zone size ≤ 30 cm)	[4.6] dB	[5.0] dB

# 6.5A.3 Spurious emissions for CA

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Testability issue for 6GHz ~ [12.75GHz] is identified. How to treat this frequency range is TBD.
- TRP Measurement Uncertainty for CA is TBD.
- TP analysis for CA is FFS (identify lowest MPR w/form, RB allocation for multiple carrier or PCC only, 1RB location if RB allocated for multiple carrier).
- Beam peak direction for CA is TBD and cannot be assumed to be the same as single carrier.
- Update all CA test config tables to RAN 5 agreed format.

## 6.5A.3.1 Transmitter Spurious emissions for CA

## 6.5A.3.1.0 Minimum conformance requirements

This clause specifies the spurious emission requirements for carrier aggregation. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid). The TX beam peak direction used for CA testing is the [same as that found for single carrier scenario in clause 6.5.3].

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

For intra-band contiguous carrier aggregation, the spurious emission limits apply for the frequency ranges that are more than  $F_{OOB}$  (MHz) from the edge of the aggregated channel bandwidth, where  $F_{OOB}$  is defined as the twice the aggregated channel bandwidth. For frequencies  $\Delta f_{OOB}$  greater than  $F_{OOB}$ , the spurious emission requirements in Table 6.5.3.1.3-2 are applicable. If carrier leakage or I/Q image lands inside the spectrum occupied by the configured UL and DL CCs, exception to the spurious emissions requirement applies. For carrier leakage the requirements specified in section 6.4A.2.3.0 shall apply. For I/Q image the requirements specified in section 6.4A.2.3.0 shall apply.

## 6.5A.3.1.1 Transmitter Spurious emissions for CA (2UL CA)

## 6.5A.3.1.1.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

# 6.5A.3.1.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

6.5A.3.1.1.3	Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

## 6.5A.3.1.1.4 Test description

6.5A.3.1.1.4.1 Initial condition

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.5A. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 6.5A.3.1.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

Table	6.5A.3.	1.1.4.1-1:	Test	Configuration Table
-------	---------	------------	------	---------------------

	Initial Conditions					
Test Enviror	Test Environment as specified in TS 38.508- Normal					
1 [10] subcla	ause 4.1					
	Test Frequencies as specified in TS 38.508- Low range, High range (NOTE 2)					
1 [10] subcla						
Test Channe	el Bandwidths as specified in TS	Maximum aggregated BW (contiguous	CA)			
	)] subclause 4.3.1					
Test SCS as	Test SCS as specified in Table 5.3.5-1 120kHz					
		Test Parameters				
Test ID	Downlink Configuration	Uplink Configuration [per o	component carrier]			
		Modulation	RB allocation			
	N/A for Spurious Emissions		(NOTE 1)			
1	testing	FFS	FFS			
2		FFS	FFS			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
6.	.1-2 for PC1.					
NOTE 2: When testing Low range test only in Frequency Range lower than $(F_{UL_{low}} - \Delta f_{OOB})$ and when testing High						
	ange test only in Frequency Range					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5A.3.1.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.3.1.1.4.3

## 6.5A.3.1.1.4.2 Test procedure

1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.

- 2. If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</p>
- 3. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 4. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.3.1.1.4.3.
- 5. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 6. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.5A.3.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 7. Set the UE in the Inband Tx beam peak direction [(same as that found for single carrier in clause 6.5.3)] found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 8. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 9. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 10. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4):
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex L, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.1.3-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.1.3-2 may be applied as long as the SNR (ratio of test limit to floor noise of test equipment)  $\geq$  10dB is guaranteed. The measurement period shall capture the [active time slots]. For each spurious emission frequency with coarse TRP identified to be less than an offset dB (NOTE 2) from the TRP limit according to Table 6.5.3.1.3-2, continue with fine TRP procedures according to step (b).

The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.

- (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.1.3-2.
- 11. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 6.5.3.1.3-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: The coarse TRP measurement grid and corresponding offset dB value referred in step 5(a) above, for some valid grids can be found in TR 38.903 section B.18.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le 0 \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le 0 \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > 0 \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < 0 \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le 0 \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > 0 \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

#### 6.5A.3.1.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 6.5A.3.1.1.5 Test Requirements

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions requirement with frequency range as indicated in Table 6.5A.3.1.1.5-1.

The maximum EIRP or TRP power of spurious emission, measured using RMS detector, shall not exceed the described value in Table 6.5A.3.1.1.5-1.

Unless otherwise stated, the spurious emission limits apply for the frequency ranges that are more than  $F_{OOB}$  (MHz) in Table 6.5.3.1.3-1 starting from the edge of the assigned *NR* channel bandwidth. The spurious emission limits in Table 6.5A.3.1.1.5-1 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

#### Table 6.5A.3.1.1.5-1: Spurious emissions for CA test requirements

Frequency Range	Maximum Level	Measurement bandwidth	NOTE
6 GHz ≤ f < 12.75 GHz	-30 dBm	1 MHz	
12.75 GHz ≤ f ≤ 2 <sup>nd</sup> harmonic of the upper frequency edge of the UL operating band in GHz	-13 dBm	1 MHz	
NOTE 1: Applies for Ban	d n257, n258, n260		

## 6.5A.3.1.2 Transmitter Spurious emissions for CA (3UL CA)

#### 6.5A.3.1.2.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

#### 6.5A.3.1.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.5A.3.1.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

#### 6.5A.3.1.2.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

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## 6.5A.3.1.2.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5.

# 6.5A.3.1.3 Transmitter Spurious emissions for CA (4UL CA)

## 6.5A.3.1.3.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

## 6.5A.3.1.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

# 6.5A.3.1.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

## 6.5A.3.1.3.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

# Table 6.5A.3.1.3.4.1-1: Test Configuration Table

### [TBD]

## 6.5A.3.1.3.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5.

## 6.5A.3.1.4 Transmitter spurious emissions for CA (5UL CA)

## 6.5A.3.1.4.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

## 6.5A.3.1.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

## 6.5A.3.1.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

6.5A.3.1.4.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

6.5A.3.1.4.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5

## 6.5A.3.1.5 Transmitter spurious emissions for CA (6UL CA)

## 6.5A.3.1.5.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

## 6.5A.3.1.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

## 6.5A.3.1.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

# 6.5A.3.1.5.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

# 6.5A.3.1.5.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5

# 6.5A.3.1.6 Transmitter spurious emissions for CA (7UL CA)

# 6.5A.3.1.6.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

# 6.5A.3.1.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

# 6.5A.3.1.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

# 6.5A.3.1.6.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

# 6.5A.3.1.6.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5

# 6.5A.3.1.7 Transmitter spurious emissions for CA (8UL CA)

# 6.5A.3.1.7.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

# 6.5A.3.1.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

# 6.5A.3.1.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.1.0.

# 6.5A.3.1.7.4 Test description

Same test description as in clause 6.5A.3.1.1.4.

## 6.5A.3.1.7.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.1.1.5

# 6.5A.3.2 Spurious emission band UE co-existence for CA

This clause specifies the requirements for the specified carrier aggregation configurations for coexistence with protected bands. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid). The TX beam peak direction used for CA testing is the [same as that found for single carrier scenario in clause 6.5.3].

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

## 6.5A.3.2.0 Minimum conformance requirements

For intra-band contiguous carrier aggregation, the requirements in Table 6.5A.3.2.0-1 apply.

UL CA for	Spurious emission							
any CA bandwidth class	Protected band / frequency range	Frequency range (MHz)			Maximum Level (dBm)	MBW (MHz)	NOTE	
	NR Band n260	F <sub>DL_low</sub>	-	$F_{DL_high}$	-2	100		
CA_n257	Frequency range	23600	•	24000	TBD	200	2	
	Frequency range	57000	1	66000	2	100		
CA_n258	Frequency range	23600	•	24000	TBD	200	2	
	Frequency range	57000	-	66000	2	100		
	NR Band 257	$F_{DL\_low}$	-	$F_{DL_high}$	-5	100		
	NR Band 261	$F_{DL_{low}}$	-	F <sub>DL_high</sub>	-5	100		
CA_n260	Frequency range	23600	-	24000	TBD	200	2	
	Frequency range	57000	-	66000	2	100		
CA n261	NR Band 260	F <sub>DL_low</sub>	-	FDL_high	-2	100		
	Frequency range	23600	-	24000	TBD	200	2	
	Frequency range	57000	-	66000	2	100		
	w and F <sub>DL_high</sub> refer to each NR frec protection of frequency range 2360 ces.					satellite pas	ssive	

# 6.5A.3.2.1 Spurious emission band UE co-existence for CA (2UL CA)

# 6.5A.3.2.1.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

# 6.5A.3.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

# 6.5A.3.2.1.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.2.0.

#### 6.5A.3.2.1.4 Test description

#### 6.5A.3.2.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

Initial Conditions						
Test Enviror	nment as specified in TS 38.508-	Normal				
1 [10] subcla	ause 4.1					
Test Freque	ncies as specified in TS 38.508-	Low range, High range (NOTE 2)				
1 [10] subcla	ause 4.3.1					
Test Channe	el Bandwidths as specified in TS	Maximum aggregated BW (contiguous C	;A)			
38.508-1 [10	)] subclause 4.3.1					
Test SCS as	s specified in Table 5.3.5-1	120kHz				
		Test Parameters				
Test ID	Test ID Downlink Configuration Uplink Configuration [per component carrier]					
		Modulation	RB allocation			
	N/A for Spurious Emissions		(NOTE 1)			
1	testing	FFS	FFS			
2		FFS	FFS			
NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table						
6.	6.1-2 for PC1.					
NOTE 2: When testing Low range test only in Frequency Range lower than ( $F_{UL_low} - \Delta f_{OOB}$ ) and when testing High						
	ange test only in Frequency Range		ioob) and mion cooling right			

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5A.3.2.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.3.2.1.4.3.

6.5A.3.2.1.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</li>
- 3. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 4. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.3.1.1.4.3.
- 5. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).

- 6. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.5A.3.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 7. Set the UE in the Inband Tx beam peak direction [(same as that found for single carrier in clause 6.5.3)] found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 8. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 9. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 10. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4):
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex L, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.1.3-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.1.3-2 may be applied as long as the SNR (ratio of test limit to floor noise of test equipment)  $\geq$  10dB is guaranteed. The measurement period shall capture the [active time slots]. For each spurious emission frequency with coarse TRP identified to be less than an offset dB (NOTE 2) from the TRP limit according to Table 6.5.3.1.3-2, continue with fine TRP procedures according to step (b).
  - The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.
  - (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.1.3-2.
- 11. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 6.5.3.1.3-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: The coarse TRP measurement grid and corresponding offset dB value referred in step 5(a) above, for some valid grids can be found in TR 38.903 section B.18.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

#### 6.5A.3.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.1.

#### 6.5A.3.2.1.5 Test requirement

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions for UE coexistence requirement with frequency range as indicated in Table 6.5A.3.2.1.5-1.

The maximum EIRP or TRP power of spurious emission for UE co-existence, measured using RMS detector, shall not exceed the described value in Table 6.5A.3.2.1.5-1.

The spurious emission UE co-existence limits in Table 6.5A.3.2.1.5-1 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

UL CA for	Spurious emission						
any CA bandwidth class	Protected band / frequency range	Frequency range (MHz)			Maximum Level (dBm)	MBW (MHz)	NOTE
	NR Band n260	$F_{DL\_low}$	I	$F_{DL_high}$	-2	100	
CA_n257	Frequency range	23600	-	24000	TBD	200	2
	Frequency range	57000	-	66000	2	100	
CA 2259	Frequency range	23600	-	24000	TBD	200	2
CA_n258	Frequency range	57000	-	66000	2	100	
	NR Band 257	F <sub>DL_low</sub>	-	$F_{DL_high}$	-5	100	
CA 2260	NR Band 261	FDL_low	-	$F_{DL_high}$	-5	100	
CA_n260	Frequency range	23600	-	24000	TBD	200	2
	Frequency range	57000	-	66000	2	100	
	NR Band 260	F <sub>DL_low</sub>	-	$F_{DL_high}$	-2	100	
CA_n261	Frequency range	23600	-	24000	TBD	200	2
	Frequency range	57000	-	66000	2	100	
<ul> <li>NOTE 1: F<sub>DL_low</sub> and F<sub>DL_high</sub> refer to each NR frequency band specified in Table 5.2-1</li> <li>NOTE 2: The protection of frequency range 23600-2400MHz is meant for protection of satellite passive services.</li> </ul>							

#### Table 6.5A.3.2.1.5-1: Spurious emissions UE co-existence CA test requirements

## 6.5A.3.2.2 Spurious emission band UE co-existence for CA (3UL CA)

## 6.5A.3.2.2.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

## 6.5A.3.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

## 6.5A.3.2.2.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

## 6.5A.3.2.2.4 Test description

Same test description as in clause 6.5A.3.2.1.4.

## 6.5A.3.2.2.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

## 6.5A.3.2.3 Spurious emission band UE co-existence for CA (4UL CA)

## 6.5A.3.2.3.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

#### 6.5A.3.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.5A.3.2.3.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

#### 6.5A.3.2.3.4 Test description

Same test description as in clause 6.5A.3.2.1.4.

## 6.5A.3.2.3.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

## 6.5A.3.2.4 Spurious emission band UE co-existence for CA (5UL CA)

## 6.5A.3.2.4.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

#### 6.5A.3.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

#### 6.5A.3.2.4.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

#### 6.5A.3.2.4.4 Test description

Same test description as in clause 6.5A.3.2.1.4.

#### 6.5A.3.2.4.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

#### 6.5A.3.2.5 Spurious emission band UE co-existence for CA (6UL CA)

## 6.5A.3.2.5.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

#### 6.5A.3.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.5A.3.2.5.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

## 6.5A.3.2.5.4 Test description

Same test description as in clause 6.5A.3.2.1.4.

## 6.5A.3.2.5.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

# 6.5A.3.2.6 Spurious emission band UE co-existence for CA (7UL CA)

## 6.5A.3.2.6.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

## 6.5A.3.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

# 6.5A.3.2.6.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

Same test description as in clause 6.5A.3.2.1.4.

# 6.5A.3.2.6.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

# 6.5A.3.2.7 Spurious emission band UE co-existence for CA (8UL CA)

# 6.5A.3.2.7.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

# 6.5A.3.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

## 6.5A.3.2.7.3 Minimum conformance requirements

The minimum conformance requirements are defined in clause 6.5A.3.2.0.

# 6.5A.3.2.7.4 Test description

Same test description as in clause 6.5A.3.2.1.4.

# 6.5A.3.2.7.5 Test Requirements

The test requirement is the same as in clause 6.5A.3.2.1.5.

# 6.5A.3.3 Additional spurious emissions for CA

# Editor's note:

Adding details for NS\_202 & NS\_203 is pending

#### 6.5A.3.3.0 Minimum conformance requirements

The additional spurious emission for CA limits in Table 6.5A.3.3.0-1 and Table 6.5A.3.3.0-2 apply for all transmitter band configurations (RB) and channel bandwidths. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

When "NS\_201" is indicated in the cell, the power of any UE emission shall not exceed the levels specified in Table 6.5A.3.3.0-1. This requirement also applies for the frequency ranges that are less than  $F_{OOB}$  (MHz) in Table 6.5.3-1 from the edge of the channel bandwidth.

Table 6.5A.3.3.0-1: Additional spurious emissions for CA (NS\_201) test limits

Frequency Range	Maximum Level / Channel bandwidth			Measurement	NOTE	
	50 MHz	100 MHz	200 MHz	400 MHz	bandwidth	
$23.6 \text{ GHz} \le f \le 24 \text{ GHz}$	-8 dBm	-8 dBm	-8 dBm	-8 dBm	200MHz	1
NOTE 1: The protection of frequency range 23600 - 24000 MHz is meant for protection of satellite passive services.						

When "NS\_202" is indicated in the cell, the power of any UE emission shall not exceed the levels specified in Table 6.5A.3.3.0-2.

Table 6.5A.3.3.0-2: Additional spurious emissions for (NS\_202) test limits

Frequency Range	Maximum Level	Measurement bandwidth
7.25 GHz $\leq$ f $\leq$ 2 <sup>nd</sup> harmonic of the upper frequency edge of the UL operating band	-10 dBm	100 MHz

The normative reference for this requirement is TS 38.101-2 subclause 6.5A.3.2.

#### 6.5A.3.3.1 Additional spurious emission for CA (2UL CA)

#### 6.5A.3.3.1.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2UL CA.

#### 6.5A.3.3.1.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

6.5A.3.3.1.4 Test description

6.5A.3.3.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the Subscriber Station (SS) to take with the UE to reach the correct measurement state.

		Initial Conditions			
Test Enviror 1 [10] subcla	nment as specified in TS 38.508- ause 4.1	Normal			
Test Frequencies as specified in TS 38.508- 1 [10] subclause 4.3.1		Low range, High range (NOTE 2)			
	el Bandwidths as specified in TS )] subclause 4.3.1	Highest			
Test SCS as	s specified in Table 5.3.5-1	120kHz			
		Test Parameters			
Test ID	Downlink Configuration	Uplink Configur	ation		
	N/A for Spurious Emissions	Modulation	RB allocation (NOTE 1)		
1	testing	FFS	FFS		
2		FFS	FFS		
<ul> <li>NOTE 1: The specific configuration of each RB allocation is defined in Table 6.1-1 for PC2, PC3 and PC4 or Table 6.1-2 for PC1.</li> <li>NOTE 2: When testing Low range test only in Frequency Range lower than (F<sub>UL_low</sub> – Δf<sub>OOB</sub>) and when testing High range test only in Frequency Range higher than (F<sub>UL_high</sub> + Δf<sub>OOB</sub>).</li> </ul>					

#### Table 6.5A.3.3.1.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5A.3.3.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5A.3.3.1.4.3.

#### 6.5A.3.3.1.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</li>
- 3. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 4. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 6.5A.3.1.1.4.3.
- 5. SS activates SCC by sending the activation MAC CE (Refer TS 38.321 [28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.3).
- 6. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 6.5A.3.1.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 7. Set the UE in the Inband Tx beam peak direction [(same as that found for single carrier in clause 6.5.3)] found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.

- 8. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 9. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 10. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4):
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex L, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 6.5.3.1.3-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 6.5.3.1.3-2 may be applied as long as the SNR (ratio of test limit to floor noise of test equipment)  $\geq$  10dB is guaranteed. The measurement period shall capture the [active time slots]. For each spurious emission frequency with coarse TRP identified to be less than an offset dB (NOTE 2) from the TRP limit according to Table 6.5.3.1.3-2, continue with fine TRP procedures according to step (b).
  - The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.
  - (b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 6.5.3.1.3-2.
- 11. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 6.5.3.1.3-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: The coarse TRP measurement grid and corresponding offset dB value referred in step 5(a) above, for some valid grids can be found in TR 38.903 section B.18.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

#### 6.5A.3.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.1.

#### 6.5A.3.3.1.5 Test requirement

This clause specifies the requirements for the specified *NR* band for Transmitter Spurious emissions for UE coexistence requirement with frequency range as indicated in Table 6.5A.3.3.1.5-1 and Table 6.5A.3.3.1.5-2.

The maximum EIRP or TRP power of spurious emission for UE co-existence, measured using RMS detector, shall not exceed the described value in Table 6.5A.3.3.1.5-1 and Table 6.5A.3.3.1.5-2.

The additional spurious emission for CA limits in Table 6.5A.3.3.1.5-1 and Table 6.5A.3.3.1.5-2 apply for all transmitter band configurations (NRB) and channel bandwidths.

NOTE: For measurement conditions at the edge of each frequency range, the lowest frequency of the measurement position in each frequency range should be set at the lowest boundary of the frequency range plus MBW/2. The highest frequency of the measurement position in each frequency range should be set at the highest boundary of the frequency range minus MBW/2. MBW denotes the measurement bandwidth defined for the protected band.

#### Table 6.5A.3.3.1.5-1: Additional spurious emissions for CA (NS\_201) test requirements

Frequency	Maximum Level / Channel bandwidth			Measurement	NOTE	
Range	50	100	200	400 MHz	bandwidth	
	MHz	MHz	MHz			
23.6 GHz ≤ f	-8 dBm	-8 dBm	-8 dBm	-8 dBm	200MHz	1
≤ 24 GHz						
NOTE 1: The protection of frequency range 23600 - 24000 MHz is meant for protection						
of sate	of satellite passive services.					

#### Table 6.5A.3.3.1.5-2: Additional spurious emissions for CA (NS\_202) test requirements

Frequency Range	Maximum Level	Measurement bandwidth
7.25 GHz $\leq$ f $\leq$ 2 <sup>nd</sup> harmonic of the upper frequency edge of the UL operating band	-10 dBm	100 MHz

#### 6.5A.3.3.2 Additional spurious emission for CA (3UL CA)

#### 6.5A.3.3.2.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3UL CA.

#### 6.5A.3.3.2.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

#### 6.5A.3.3.2.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

#### 6.5A.3.3.2.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5

#### 6.5A.3.3.3 Additional spurious emission for CA (4UL CA)

#### 6.5A.3.3.3.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.2. Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4UL CA.

#### 6.5A.3.3.3.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

#### 6.5A.3.3.3.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

#### 6.5A.3.3.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5.

#### 6.5A.3.3.4 Additional spurious emission for CA (5UL CA)

#### 6.5A.3.3.4.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5UL CA.

6.5A.3.3.4.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

#### 6.5A.3.3.4.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

#### 6.5A.3.3.4.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5.

#### 6.5A.3.3.5 Additional spurious emission for CA (6UL CA)

#### 6.5A.3.3.5.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6UL CA.

#### 6.5A.3.3.5.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

#### 6.5A.3.3.5.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

#### 6.5A.3.3.5.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5.

## 6.5A.3.3.6 Additional spurious emission for CA (7UL CA)

## 6.5A.3.3.6.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7UL CA.

6.5A.3.3.6.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

6.5A.3.3.6.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

#### 6.5A.3.3.6.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5.

#### 6.5A.3.3.7 Additional spurious emission for CA (8UL CA)

#### 6.5A.3.3.7.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

#### 6.5A.3.3.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 8UL CA.

6.5A.3.3.7.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 6.5A.3.3.0.

6.5A.3.3.7.4 Test description

Same test description as in clause 6.5A.3.3.1.4.

6.5A.3.3.7.5 Test requirement

The test requirement is the same as in clause 6.5A.3.3.1.5

## 6.5D Output RF spectrum emissions for UL MIMO

## 6.5D.1 Occupied bandwidth for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation
- Measurement Uncertainty is FFS
- 38.905 TP for UL MIMO is pending
- Applicability of UBF of single UL is FFS

### - Applicability of Beam peak of single UL is FFS

#### 6.5D.1.1 Test purpose

To verify that the UE occupied bandwidth for all transmission bandwidth configurations supported by the UE supporting UL MIMO are less than their specific limits when UE is configured using UL MIMO transmission.

## 6.5D.1.2 Test applicability

This test applies to all types of NR UE release 15 and forward that supporting UL MIMO.

## 6.5D.1.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 6.5.1.3. The requirements shall be met with the UL MIMO configurations specified in Table 6.5D.1.3-1.

## Table 6.5D.1.3-1: UL MIMO configuration

Transmission scheme	DCI format	TPMI Index
Codebook based uplink	DCI format 0_1	0

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.1.

## 6.5D.1.4 Test description

## 6.5D.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.2-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and subcarrier spacing, are shown in table 6.5D.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

## Table 6.5D.1.4.1-1: Test Configuration Table

FFS

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and clause A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] clause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.0, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.5D.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.5D.1.4.3

## 6.5D.1.4.2 Test procedure

1. SS sends uplink scheduling information for each UL HARQ process via PDSCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.5D.1.4.1-1. Since the UL has no payload and no loopback data to

send the UE sends uplink MAC padding bits on the UL RMC. The PDCCH DCI format 0\_1 is specified with condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2

- 2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 ms for the UE to reach maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure the EIRP spectrum distribution within two times or more frequency range over the requirement for Occupied Bandwidth specification centring on the current carrier frequency. The characteristics of the filter shall be approximately Gaussian (typical spectrum analyser filter). The measuring duration is one active uplink subframe. EIRP is captured from both polarizations, theta and phi.
- 6. Calculate the total EIRP from both polarizations, theta and phi, within the range of all frequencies measured in step 5 and save this value as "Total EIRP". EIRP measurement procedure is defined in Annex K.
- 7. Identify the measurement window whose centre is aligned on the centre of the channel for which the sum of the power measured in theta and phi polarization is 99% of the "Total EIRP".
- 8. The "Occupied Bandwidth" is the width of the measurement window obtained in step 7.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 6.5D.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

6.5D.1.5 Test requirement

The measured Occupied Bandwidth shall not exceed values in Table 6.5D.1.5-1.

	Occupied cr	nannei ban	dwidth / Cha	nnel bandwidth
	50	100	200	400
	MHz	MHz	MHz	MHz
Channel bandwidth (MHz)	50	100	200	400

#### Table 6D.5.1.5-1: Occupied channel bandwidth

## 6.5D.2 Out of band emission for UL MIMO

## 6.5D.2.1 Spectrum Emission Mask for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation
- TRP Measurement Uncertainty is FFS.
- 39.905 TP analysis for UL MIMO is pending
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

6.5D.2.1.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth. 6.5D.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

6.5D.2.1.3 Minimum conformance requirements

For UE(s) supporting UL MIMO, the Spectrum Emission Mask requirements in clause 6.5.2.1.3 apply. The requirements shall be met with the UL MIMO configurations specified in Table 6.2D.1.3-3.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.2.

6.5D.2.1.4 Test description

6.5D.2.1.4.1 Initial condition

Same initial condition in clause 6.5.2.1.4.1.

6.5D.2.1.4.2 Test procedure

Same test procedure as in clause 6.5.2.1.4.2.

6.5D.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

6.5D.2.1.5 Test requirements

The test requirement is the same as in clause 6.5.2.1.5.

#### 6.5D.2.2 Adjacent channel leakage ratio for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation
- TRP Measurement Uncertainty is FFS.
- 39.905 TP analysis for UL MIMO is pending
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

#### 6.5D.2.2.1 Test purpose

To verify that the power of any UE emission shall not exceed specified lever for the specified channel bandwidth.

#### 6.5.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

#### 6.5D.2.2.3 Minimum conformance requirements

For UE(s) supporting UL MIMO, the Adjacent channel leakage ratio requirements in clause 6.5.2.3.3 apply. The requirements shall be met with the UL MIMO configurations specified in Table 6.2D.1.3-3.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.2.

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## 6.5D.2.2.4 Test description

6.5D.2.2.4.1 Initial condition

Same initial condition in clause 6.5.2.3.4.1.

6.5D.2.2.4.2 Test procedure

Same test procedure as in clause 6.5.2.3.4.2.

## 6.5D.2.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition  $2TX\_UL\_MIMO$ .

## 6.5D.2.2.5 Test requirements

The test requirement is the same as in clause 6.5.2.3.5.

## 6.5D.3 Spurious emissions for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation
- TRP Measurement Uncertainty is FFS.
- 39.905 TP analysis for UL MIMO is pending
- Applicability of UBF of single UL is FFS.
- Applicability of Beam peak of single UL is FFS.

## 6.5D.3.1 Transmitter Spurious emissions for UL MIMO

## 6.5D.3.1.1 Test purpose

To verify that UE transmitter does not cause unacceptable interference to other channels or other systems in terms of transmitter spurious emissions.

## 6.5D.3.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

## 6.5D.3.1.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 6.5.3.1.3. The requirements shall be met with the UL MIMO configurations specified in Table 6.5D.3.1.3-1.

## Table 6.5D.3.1.3-1: UL MIMO configuration

Γ	Transmission scheme	DCI format	TPMI Index
	Codebook based uplink	DCI format 0_1	0

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.3.

## 6.5D.3.1.4 Test description

#### 6.5D.3.1.4.1 Initial condition

Same initial condition in clause 6.5.3.1.4.1.

### 6.5D.3.1.4.2 Test procedure

Same test procedure as in clause 6.5.3.1.4.2 with the following added to step 3 for UL MIMO configuration:

3.1 The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.

## 6.5D.3.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

## 6.5D.3.1.5 Test requirements

The test requirement is the same as in clause 6.5.3.1.5.

## 6.5D.3.2 Spurious emission band UE co-existence for UL MIMO

## 6.5D.3.2.1 Test purpose

To verify that UL MIMO configured UE's transmitter does not cause unacceptable interference when in co-existence with protected bands in terms of transmitter spurious emissions.

### 6.5D.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

## 6.5D.3.2.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 6.5.3.2.3. The requirements shall be met with the UL MIMO configurations specified in Table 6.5D.3.1.3-1.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.3.

6.5D.3.2.4 Test description

6.5D.3.2.4.1 Initial condition

Same initial condition in clause 6.5.3.2.4.1.

6.5D.3.2.4.2 Test procedure

Same test procedure as in clause 6.5.3.2.4.2 with the following added to step 3 for UL MIMO configuration:

3.1 The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.

### 6.5D.3.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

6.5D.3.2.5 Test requirements

The test requirement is the same as in clause 6.5.3.2.5.

## 6.5D.3.3 Additional Spurious emission for UL MIMO

#### 6.5D.3.3.1 Test purpose

Additional spurious emission requirements are signalled by the network to indicate that the UE shall meet an additional requirement for a specific deployment scenario as part of the cell handover/broadcast message.

6.5D.3.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

#### 6.5D.3.3.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 6.5.3.3.3. The requirements shall be met with the UL MIMO configurations specified in Table 6.5D.3.1.3-1.

The normative reference for this requirement is TS 38.101-2 [3] clause 6.5D.3.

6.5D.3.3.4	Test descriptior
0.00.3.3.4	

6.5D.3.3.4.1 Initial condition

Same initial condition in clause 6.5.3.3.4.1.

#### 6.5D.3.3.4.2 Test procedure

Same test procedure as in clause 6.5.3.3.4.2 with the following added to step 3 for UL MIMO configuration:

3.1 The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.

#### 6.5D.3.3.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

#### 6.5D.3.3.5 Test requirements

The test requirement is the same as in clause 6.5.3.3.5.

## 6.6 Beam correspondence

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are FFS for power class 3.

## 6.6.0 General

Beam correspondence is the ability of the UE to select a suitable beam for UL transmission based on DL measurements with or without relying on UL beam sweeping. The beam correspondence requirement is satisfied assuming the presence of both SSB and CSI-RS signal and Type D QCL is maintained between SSB and CSI-RS.

## 6.6.1 Beam correspondence - EIRP

#### 6.6.1.1 Test purpose

To verify the UE's ability to select a suitable beam for UL transmission based on DL measurements with or without relying on UL beam sweeping within the range prescribed by the specified nominal maximum output power and beam correspondence tolerance.

## 6.6.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that does not support beam correspondence without UL beam sweeping.

6.6.1.3	Minimum	conformance	requirements

6.6.1.3.1	(Void)
-----------	--------

6.6.1.3.2 (Void)

6.6.1.3.3 Beam correspondence for PC3

6.6.1.3.3.1 General

The beam correspondence requirement for PC3 UEs consists of three components: UE minimum peak EIRP (as defined in clause 6.2.1.1.3.3), UE spherical coverage (as defined in clause 6.2.1.1.3.3), and beam correspondence tolerance (as defined in clause 6.6.1.3.3.2). The beam correspondence requirement is fulfilled if the UE satisfies one of the following conditions, depending on the UE's beam correspondence capability IE *beamCorrespondenceWithoutUL-BeamSweeping*, as defined in TS 38.306 [26]:

- If *beamCorrespondenceWithoutUL-BeamSweeping* is supported, the UE shall meet the minimum peak EIRP requirement according to Table 6.2.1.3-1 and spherical coverage requirement according to Table 6.2.1.3-3 with its autonomously chosen UL beams and without uplink beam sweeping. Such a UE is considered to have met the beam correspondence tolerance requirement.
- If *beamCorrespondenceWithoutUL-BeamSweeping* is not present, the UE shall meet the minimum peak EIRP requirement according to Table 6.2.1.3-1 and spherical coverage requirement according to Table 6.2.1.3-3 with uplink beam sweeping. Such a UE shall meet the beam correspondence tolerance requirement defined in Clause 6.6.4.2 and shall support uplink beam management, as defined in TS 38.306 [26].

## 6.6.1.3.3.1.1 Side condition for SSB and CSI-RS

The beam correspondence requirements are only applied under the following conditions:

- The downlink reference signals including both SSB and CSI-RS are provided and Type D QCL shall be maintained between SSB and CSI-RS.
- The reference measurement channel for beam correspondence are fulfilled according to the CSI-RS configuration in Annex A.3.
- The beam correspondence conditions for L1-RSRP measurements are fulfilled according to Table 6.6.1.3.3.1.1-1 and Table 6.6.1.3.3.1.1-2.

#### Table 6.6.1.3.3.1.1-1: Conditions for SSB based L1-RSRP measurements for beam correspondence

		Minimum SSB_RP Note 2	SSB Ês/lot	
Angle of	NR operating	dBm / SCS <sub>SSB</sub>		
arrival	bands	SCS <sub>SSB</sub> = 120 kHz	dB	
	n257	-96.4		
All angles	n258	-96.4	≥6	
Note 1	n260	-92.1		
	n261	-96.4		
Note 1: For UEs that support multiple FR2 bands, the Minimum SSB_RP values for all angles are increased by ΣMB <sub>s</sub> , the UE multi-band relaxation factor in dB specified in TS 38.101-2 [3] clause 6.2.1.				
	Values specified at the radiated requirements reference point to give minimum SSB Ês/lot, with no applied noise.			

#### Table 6.6.1.3.3.1.1-2: Conditions for CSI-RS based L1-RSRP measurements for beam correspondence

	Minimum CSI-RS_RP Note 2		CSI-RS Ês/lot	
Angle of		dBm / SCS <sub>CSI-RS</sub>		
arrival	NR operating bands	SCS <sub>CSFRS</sub> = 120 kHz	dB	
n257		-96.4		
All angles	n258	-96.4	≥6	
Note 1	n260	-92.1		
	n261	-96.4		
<ul> <li>Note 1: For UEs that support multiple FR2 bands, the Minimum CSI-RS_RP values for all angles are increased by ΣMBs, the UE multi-band relaxation factor in dB specified in TS 38.101-2 [3] clause 6.2.1.</li> <li>Note 2: Values specified at the radiated requirements reference point to give minimum CSI-RS Ês/lot, with no applied noise.</li> </ul>				

#### 6.6.1.3.3.2 Beam correspondence tolerance for PC3

The beam correspondence tolerance requirement  $\Delta EIRP_{BC}$  for power class 3 UEs is defined based on a percentile of the distribution of  $\Delta EIRP_{BC}$ , defined as  $\Delta EIRP_{BC} = EIRP_2 - EIRP_1$  over the link angles spanning a subset of the spherical coverage grid points, such that

- EIRP<sub>1</sub> is the total EIRP in dBm calculated based on the beam the UE chooses autonomously (corresponding beam) to transmit in the direction of the incoming DL signal, which is based on beam correspondence without relying on UL beam sweeping.
- EIRP<sub>2</sub> is the best total EIRP (beam yielding highest EIRP in a given direction) in dBm which is based on beam correspondence with relying on UL beam sweeping.
- The link angles are the ones corresponding to the top  $N^{th}$  percentile of the EIRP<sub>2</sub> measurement over the whole sphere, where the value of N is according to the test point of EIRP spherical coverage requirement for power class 3, i.e. N = 50.

For power class 3 UEs, the requirement is fulfilled if the UE's corresponding UL beams satisfy the maximum limit in Table 6.6.1.3.3.2-1.

Operating band	Max ∆EIRP <sub>BC</sub> at 85 %-tile ∆EIRP <sub>BC</sub> CDF (dB)
n257	3.0
n258	3.0
n260	3.2
n261	3.0
NOTE: The requirements in this table are verified only under normal temperature conditions as defined in Annex E.2.1	

Table 6.6.1.3.3.2-1: UE beam correspondence tolerance for power class 3

### 6.6.1.3.4 Normative reference

The normative reference for this requirement is TS 38.101-2 [3] clause 6.6.

#### 6.6.1.4 Test description

#### 6.6.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in Table 6.6.1.4.1-1. The details of the uplink reference measurement channels (RMCs) are specified in Annexes A.2. The downlink reference measurement channels (RMCs) are specified in Annexes A.2. The downlink reference measurement are specified in Annex C.2.

	Default Conditions						
Test Environment as specified in TS 38.508-1 [10]			Normal				
subclause [4.1]							
Test Frequencies as specified in TS 38.508-1 [10]			Low range, High range				
subclau	ise [4.3.1]						
			specified in TS 38.	508-	Lowest, Highest		
	ubclause [4						
Test SC	CS as speci	fied in Tab	le 5.3.5-1		120 kHz		
			Test P	aram	eters		
Test	ChBw	SCS	Downlink		Uplink C	onfiguration	
ID			Configuration				
		Default	N/A		Modulation	RB allocation (NOTE 1)	
1	50			DF	DFT-s-OFDM QPSK Inner_Full		
2	100						
3	200						
4	400						
NOTE '	1: The spe	cific config	uration of each RF	alloca	tion is defined in Ta	able 6.1-1.	

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.2 and TS 38.508-1 [10] subclause 5.2.1.1.1, and uplink signals according to Annex G.0, G.1 and G.3.0.
- 4. The UL Reference Measurement channels are set according to Table 6.6.1.4.1-1.
- 5. Propagation conditions are set according to Annex B.0
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 6.6.1.4.3.

#### 6.6.1.4.2 Test procedure

Test procedure without beam sweeping:

- 1.1 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.6.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.6.1.4.3.
- 1.2. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1 without uplink beam sweeping. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 1.3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 1.4. Measure UE EIRP<sub>1</sub> in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP<sub>1</sub> measurement for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.9 without beam sweeping for all the points in the grid. After a rotation, allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for UE to find the best beam to use.

The measuring duration is one active uplink subframe. EIRP<sub>1</sub> is calculated considering both polarizations, theta and phi.

1.5 Record all the measured EIRP<sub>1</sub>values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

Test procedure with beam sweeping:

- 2.1 SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format 0\_1 for C\_RNTI to schedule the UL RMC according to Table 6.6.1.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC. Messages to configure the appropriate uplink modulation in section 6.6.1.4.3.
- 2.3. Set the UE in the Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 2.2. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec to ensure that the UE transmits at its maximum output power. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 2.4. Measure UE EIRP in the Tx beam peak direction in the channel bandwidth of the radio access mode according to the test configuration. Repeat EIRP measurements for all directions in the sphere according to EIRP measurement procedure defined in Annex K.1.9 with beam sweeping. After a rotation, allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for UE to find the best beam to use. The measuring duration is one active uplink subframe. EIRP is calculated considering both polarizations, theta and phi.
- 2.5. Record all the measured EIRP<sub>2</sub> values.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

- 2.6. Calculate the  $\Delta EIRP_{BC} = EIRP_2 EIRP_1$ .
- 2.7. Calculate a cumulative distribution function for the  $\Delta EIRP_{BC}$  values.
- NOTE 2: The  $\Delta$ EIRP<sub>target-CDF</sub> is then obtained from the Cumulative Distribution Function (CDF) computed using  $\Delta$ EIRP<sub>BC</sub> for each of all top N<sup>th</sup> percentile of the EIRP<sub>2</sub> measurement points in the grid. When using constant step size measurement grids, a theta-dependent correction shall be applied, i.e., the PDF probability contribution for each measurement point is scaled by sin( $\theta$ ) or the normalized Clenshaw-Curtis weights W( $\theta$ )/W(90°), introduced in Section M.4.2.1.

#### 6.6.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with following exceptions:

#### Table 6.6.1.4.3-1: SRS-Config: SpatialRelationInfo test requirement for with beam sweeping

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table 4.6.3-182					
Information Element	Comment	Condition			
spatialRelationInfo	Not present	The UE can consider the UL beam sweeping.			

#### Table 6.6.1.4.3-2: SRS-Config: SpatialRelationInfo test requirement for without beam sweeping

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table 4.6.3-182					
Information Element Value/remark Comment Condit					
spatialRelationInfo	SRS-SpatialRelationInfo	The UE consider			
		autonomous			
		beam selection			

## Table 6.6.1.4.3-3: SRS-Config: ssb-Index test requirement for without beam sweeping

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table 4.6.3-182				
Information Element Value/remark Comment Cond			Condition	
ssb-Index	SSB-Index			

## Table 6.6.1.4.3-4: SRS-Config: SRS resources test requirement for with beam sweeping

Value/remark Not present	Comment	Condition
Not present		
2 entries	1 set with 8 SRS resources using 'beamManageme nt' plus 1 set with 1 semi- persistent SRS	
	'codebook'	
	For the 'beamManageme nt' resource set	
beamManagement		
aperiodic		
	For the semi- persistent SRS resource set	
codebook		
semi-persistent		
Not present		
9	correspondence SRS resource upper limit (M) = 8 in Rel-15 for the 'beamManageme nt' SRS Resource set plus 1 resource for the semi-persistent SRS 'codebook'	
	aperiodic codebook semi-persistent	'beamManageme         nt' plus         1 set with 1 semi-persistent SRS         resource using         'codebook'         For the         'beamManagement         aperiodic         aperiodic         For the semi-persistent SRS         resource set         codebook         semi-persistent         Not present         9         The default beam correspondence         SRS resource         upper limit (M) = 8         in Rel-15 for the         'beamManageme         nt' SRS Resource         set plus         1 resource for the         semi-persistent

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Tab	le 4.6.3-45		
Information Element	Value/remark	Comment	Condition
CSI-RS-ResourceMapping ::= SEQUENCE {			
frequencyDomainAllocation CHOICE {			
row1	0001	k0 = 0, row1,	
		1Tx test cases	
}			
nrofPorts	p1	1Tx test cases	
firstOFDMSymbolInTimeDomain	6 for resource #0		
	7 for resource #1		
	8 for resource #2		
	9 for resource #3		
	10 for resource #4		
	11 for resource #5		
	12 for resource #6		
	13 for resource #7		
cdm-Type	noCDM		
density CHOICE {			
three	NULL		
}			
freqBand	CSI-		
	FrequencyOccupation		
}			

Table 6.6.1.4.3-5: CSI-RS-ResourceMapping: CSI-RS test requirements

#### Table 6.6.1.4.3-6: NZP-CSI-RS-Resource: CSI-RS test requirements

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Ta	ble 4.6.3-85		
Information Element	Value/remark	Comment	Condition
NZP-CSI-RS-Resource ::= SEQUENCE {			
nzp-CSI-RS-ResourceId	NZP-CSI-RS-Resourceld		
resourceMapping	CSI-RS- ResourceMapping		
powerControlOffset	0		
powerControlOffsetSS	db0		
scramblingID	ScramblingId		
periodicityAndOffset	CSI- ResourcePeriodicityAnd Offset		
qcl-InfoPeriodicCSI-RS }	TCI-StateId		

## Table 6.6.1.4.3-7: NZP-CSI-RS-ResourceSet: CSI-RS test requirements

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table 4	4.6.3-87		
Information Element	Value/remark	Comment	Condition
NZP-CSI-RS-ResourceSet ::= SEQUENCE {			
nzp-CSI-ResourceSetId	NZP-CSI-RS-		
	ResourceSetId		
nzp-CSI-RS-Resources SEQUENCE (SIZE	[1 entry]		
(1maxNrofNZP-CSI-RS-ResourcesPerSet)) OF {			
NZP-CSI-RS-ResourceId[1]	NZP-CSI-RS-Resourceld		
}			
repetition	on		
aperiodicTriggeringOffset	0	Depending on UE capability	
trs-Info	Not present		
}			

Derivation Path: TS 38.508-1 [10], clause 4.6.3, T	able 4.6.3-86		
Information Element	Value/remark	Comment	Condition
NZP-CSI-RS-ResourceId	30 for resource #0		
	31 for resource #1		
	32 for resource #2		
	33 for resource #3		
	34 for resource #4		
	35 for resource #5		
	36 for resource #6		
	37 for resource #7		

Table 6.6.1.4.3-8: NZP-CSI-RS-Resourceld: CSI-RS test requirements

## Table 6.6.1.4.3-9: CSI-ResourceConfig: CSI-RS test requirements

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table	4.6.3-39		
Information Element	Value/remark	Comment	Condition
CSI-ResourceConfig ::= SEQUENCE {			
csi-ResourceConfigId	CSI-ResourceConfigId		
csi-RS-ResourceSetList CHOICE {			
nzp-CSI-RS-SSB SEQUENCE {			
nzp-CSI-RS-ResourceSetList SEQUENCE (SIZE	2 entries		
(1maxNrofNZP-CSI-RS-ResourceSetsPerConfig)) OF {			
NZP-CSI-RS-ResourceSetId[0]	0		
NZP-CSI-RS-ResourceSetId[1]	1		
}			
csi-SSB-ResourceSetList	Not present		
}			
}			
bwp-Id	BWP-Id		
resourceType	aperiodic		
}			

#### Table 6.6.1.4.3-10: CSI-FrequencyOccupation: CSI-RS test requirements

Derivation Path: TS 38.508-1 [10], clause 4.6.3, Table 4.6.3-33			
Information Element	Value/remark	Comment	Condition
CSI-FrequencyOccupation ::= SEQUENCE {			
startingRB	0		
nrofRBs	48		FR2_≥100MHz
	32		FR2_50MHz
}			

## 6.6.1.5 Test requirements

The defined %-tile EIRP in measurement distribution derived in step 2.6 shall exceed the values specified in Table 6.2.1.2.5-3 in clause 6.2.1.2.5. The defined %-tile  $\Delta$ EIRP<sub>BC</sub> in measurement distribution derived in step 2.7 shall not exceed the values specified in Table 6.6.1.5-1.

Operating band	Max ∆EIRP <sub>BC</sub> at 85 <sup>th</sup> %-tile ∆EIRP <sub>BC</sub> CDF (dB)
n257	3.0 +TT
n258	3.0 +TT
n260	3.2 +TT

Table 6.6.1.5-1: UE beam correspondence tolerance for power class 3

I	n260 3.2 +TT	
n261		3.0 +TT
NOTE:	only under n	nents in this table are verified ormal temperature conditions as \$ 38.101-2 [3] Annex E.2.1

# 6.6A Beam correspondence for CA

For intra-band CA in FR2, the same beam correspondence relationship for beam management is supported across CCs in Rel-15 and no requirement is specified. Beam correspondence performance for intra-band CA is fulfilled if the beam correspondence requirements defined in section 6.6 is met for non-CA case.6

# 7 Receiver characteristics

# 7.1 General

Editor's Note: Test configurations/environments that require new spherical scan shall be included in test procedure section and identifying such scenarios is currently FFS and owned by RAN5.

Unless otherwise stated, the receiver characteristics are specified over the air (OTA). The reference receive sensitivity (REFSENS) is defined assuming a 0 dBi reference antenna located at the centre of the quiet zone.

For Rx test cases the identified beam peak direction can be stored and reused for a device under test in various configurations/environments for the full duration of device testing as long as beam peak direction is the same.

Unless otherwise stated, Channel Bandwidth shall be prioritized in the selecting of test points. Subcarrier spacing shall be selected after Test Channel Bandwidth is selected.

The UE under test shall be pre-configured with UL Tx diversity schemes disabled to account for single polarization System Simulator (SS) in the test environment. The UE under test may transmit with dual polarization.

## 7.2 Diversity characteristics

FFS

## 7.3 Reference sensitivity

## 7.3.1 General

The reference sensitivity power level REFSENS is the EIS level (total component) at the centre of the quiet zone in the RX beam peak direction, at which the throughput shall meet or exceed the requirements for the specified reference measurement channel.

## 7.3.2 Reference sensitivity power level

Editor's note: The following aspects of the clause are for future consideration:

- Measurement Uncertainties and Test Tolerances are FFS for power class 1,2 and 4.
- The test case is incomplete for band n259.

The following aspects of the clause are for future consideration:

- The 3D EIS scan test time optimization in RAN 4/ RAN 5 is FFS (existing EIS based test time needs to be reevaluated for 200/266 grid points).
- Measurement Uncertainty is FFS for ETC
- Statistical model in Annex H.2 (currently based on LTE model) needs to be validated to confirm that it is also applicable for FR2

## 7.3.2.1 Test purpose

To verify the UE's ability to receive data with a given average throughput for a specified reference measurement channel, under conditions of low signal level, ideal propagation and no added noise.

A UE unable to meet the throughput requirement under these conditions will decrease the effective coverage area of an g-NodeB.

## 7.3.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

## 7.3.2.3 Minimum conformance requirements

The reference sensitivity power level REFSENS is defined as the EIS level at the centre of the quiet zone in the RX beam peak direction, at which the throughput shall meet or exceed the requirements for the specified reference measurement channel.

## 7.3.2.3.1 Reference sensitivity power level for power class 1

The throughput shall be  $\geq$  95 % of the maximum throughput of the reference measurement channels as specified in Annex A3.2 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal) with peak reference sensitivity specified in Table 7.3.2.1-1. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

Operating		REFSENS (dBm) / Channel bandwidth		
band	50 MHz	100 MHz	200 MHz	400 MHz
n257	-97.5	-94.5	-91.5	-88.5
n258	-97.5	-94.5	-91.5	-88.5
n260	-94.5	-91.5	-88.5	-85.5
n261	-97.5	-94.5	-91.5	-88.5
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4				

Table 7.3.2.3.1-1: Reference sensitivity for power class 1

The REFSENS requirement shall be met for an uplink transmission using QPSK DFT-s-OFDM waveforms and for uplink transmission bandwidth less than or equal to that specified in Table 7.3.2.3.1-2.

Operating	NR Band / Channel bandwidth / NRB / SCS / Duplex mode					
Operating band	50 MHz	100 MHz	200 MHz	400 MHz	SCS	Duplex Mode
n257	32	64	128	256	120 kHz	TDD
n258	32	64	128	256	120 kHz	TDD
n260	32	64	128	256	120 kHz	TDD
n261	32	64	128	256	120 kHz	TDD

Unless given by Table 7.3.2.3.1-3, the minimum requirements for reference sensitivity shall be verified with the network signalling value NS\_200 (Table 6.2.3-1) configured.

## Table 7.3.2.3.1-3: Network signalling value for reference sensitivity

Operating band	Network Signalling value
n258	NS_201

#### 7.3.2.3.2 Reference sensitivity power level for power class 2

The throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A.3.2 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal) with peak reference sensitivity specified in Table 7.3.2.3.2-1. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

Operating band		REFSENS (dBm) /	Channel bandwidth	
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-94.5	-91.5	-88.5	-85.5
n258	-94.5	-91.5	-88.5	-85.5
n261	-94.5	-91.5	-88.5	-85.5
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4				

Table 7.3.2.3.2-1: Reference	sensitivity for power	class 2
------------------------------	-----------------------	---------

The REFSENS requirement shall be met for an uplink transmission using QPSK DFT-s-OFDM waveforms and for uplink transmission bandwidth less than or equal to that specified in Table 7.3.2.3.1-2.

Unless given by Table 7.3.2.3.1-3, the minimum requirements for reference sensitivity shall be verified with the network signalling value NS\_200 (Table 6.2.3-1) configured.

#### 7.3.2.3.3 Reference sensitivity power level for power class 3

The throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A.3.2 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal) with peak reference sensitivity specified in Table 7.3.2.3-1. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

For the power class 3 UEs that support multiple FR2 bands, the minimum requirement for Reference sensitivity in Table 7.3.2.3.3-1 shall be increased per band, respectively, by the reference sensitivity relaxation parameter  $\sum MB_P$  and  $\Delta MB_{P,n}$  as specified in Table 7.3.2.3.3-1a and 7.3.2.3.3-1b.

Operating band		REFSENS (dBm) / Cha	nnel bandwidth	
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-88.3	-85.3	-82.3	-79.3
n258	-88.3	-85.3	-82.3	-79.3
n259	-84.7	-81.7	-78.7	-75.7
n260	-85.7	-82.7	-79.7	-76.7
n261	-88.3	-85.3	-82.3	-79.3
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4				

#### Table 7.3.2.3.3-1: Reference sensitivity for power class 3

Supported bands	∑MB <sub>P</sub> (dB)	∑MBs (dB)		
n257, n258	≤ 1.3	≤ 1.25		
n257, n260	≤ 1.0	≤ 0.75 <sup>3</sup>		
n258, n260	≤ 1.0	≤ 0.75 <sup>3</sup>		
n258, n261	≤ 1.0	≤ 1.25		
n260, n261	0.0	≤ 0.75 <sup>2</sup>		
n257, n258, n260	≤ 1.7	≤ 1.75 <sup>3</sup>		
n257, n258, n261	≤ 1.7	≤ 1.75		
n257, n260, n261	≤ 0.5	≤ 1.25 <sup>3</sup>		
n258, n260, n261	≤ 1.5	≤ 1.25 <sup>3</sup>		
n257, n258, n260, n261	≤ 1.7	≤ 1.75 <sup>3</sup>		
NOTE 1: The requirements in this table are applicable to UEs which support only the				
indicated bands				
NOTE 2: For supported bands n260 + n261, $\Delta MB_{S,n}$ is not applied for band n260				
NOTE 3: For n260, maximum applicable $\Delta MB_{S,n}$ is 0.4 dB and $\Delta MB_{P,n}$ is 0.75 dB				
NOTE 4: For all bands except n260, the maximum applicable $\Delta MB_{P,n}$ and $\Delta MB_{S,n}$ is				
0.75 dB				

Table 7.3.2.3.3-1a: UE multi-band relaxation factors for power class 3 (Rel-15)

Band	ΔMB <sub>P,n</sub> (dB)	∆MB <sub>s,n</sub> (dB)		
n257	0.7 <sup>3</sup>	0.7 <sup>3</sup>		
n258	0.6	0.7		
n259	0.5	0.4		
n260	0.5 <sup>1</sup>	0.4 <sup>1</sup>		
n261	0.5 <sup>2,4</sup>	0.74		
<ul> <li>NOTE 1: n260 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n260</li> <li>NOTE 2: n261 peak relaxation is 0 dB for UE that exclusively supports n261+n260</li> <li>NOTE 3: n257 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n257</li> <li>NOTE 4: n261 peak and spherical relaxations are 0 dB for UE that exclusively supports n261+n257</li> </ul>				

The REFSENS requirement shall be met for an uplink transmission using QPSK DFT-s-OFDM waveforms and for uplink transmission bandwidth less than or equal to that specified in Table 7.3.2.3.1-2.

Unless given by Table 7.3.2.3.1-3, the minimum requirements for reference sensitivity shall be verified with the network signalling value NS\_200 (Table 6.2.3-1) configured.

#### 7.3.2.3.4 Reference sensitivity power level for power class 4

The throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A.3.2 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal) with peak reference sensitivity specified in Table 7.3.2.3.4-1. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

Operating band	REFSENS (dBm) / Channel bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-97.0	-94.0	-91.0	-88.0
n258	-97.0	-94.0	-91.0	-88.0
n260	-95.0	-92.0	-89.0	-86.0
n261	-97.0	-94.0	-91.0	-88.0
NOTE 1: The transmitter shall be set to Pumax as defined in subclause 6.2.4				

Table 7.3.2.3.4-1: Reference sensitivity for power class 4

The REFSENS requirement shall be met for an uplink transmission using QPSK DFT-s-OFDM waveforms and for uplink transmission bandwidth less than or equal to that specified in Table 7.3.2.3.1-2.

Unless given by Table 7.3.2.3.1-3, the minimum requirements for reference sensitivity shall be verified with the network signalling value NS\_200 (Table 6.2.3-1) configured.

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3.2.

#### 7.3.2.4 Test description

#### 7.3.2.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth, and are shown in Table 7.3.2.4.1-1, Table 7.3.2.4.1-2, and Table 7.3.2.4.1-3 The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 7.3.2.4.1-1: Test Configuration Table

	Initial Conditions					
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal, TL/VL, TL/VH, TH/VL, TH/VH			
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Low range, Mid range, High range			
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1			Lowest, 100MHz, Highest			
Test SCS	as specified in Table 5.	3.5-1	120kHz			
		Test Para	meters			
Test ID	Downlink Co	onfiguration	Uplink Configuration			
	Modulation	RB allocation	Modulation	RB allocation		
1	CP-OFDM QPSK	Full RB (NOTE 1)	DFT-s-OFDM QPSK	REFSENS (NOTE 2)		
NOTE 1: Full RB allocation shall be used per each SCS and channel BW as specified in Table 7.3.2.4.1-2. NOTE 2: REFSENS refers to Table 7.3.2.4.1-3 which defines uplink RB configuration and start RB location for each SCS, channel BW and NR band.						

Channel Bandwidth	SCS kHz	LCRBmax	RB allocation (LCRB@RBstart)	
50MHz	120	32	32@0	
100MHz	120	66	66@0	
200MHz	120	132	132@0	
400MHz	120	264	264@0	
NOTE 1: Test Channel Bandwidths are checked separately for each NR band, the applicable channel bandwidths are specified in Table 5.3.5-1.				

#### Table 7.3.2.4.1-3: Uplink configuration for reference sensitivity, LCRB@RBstart format

Operating Band	SCS kHz	50 MHz	100 MHz	200 MHz	400 MHz	Duplex Mode
n257	120	32@0	64@0	128@0	256@0	TDD
n258	120	32@0	64@0	128@0	256@0	TDD
n260	120	32@0	64@0	128@0	256@0	TDD
n261	120	32@0	64@0	128@0	256@0	TDD

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.1, and uplink signals according to Annex G.0, G.1 and G.3.1.
- 4. The UL Reference Measurement channels are set according to Table 7.3.2.4.1-1, Table 7.3.2.4.1-2, and Table 7.3.2.4.1-3.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 7.3.2.4.3.

#### 7.3.2.4.2 Test procedure

- 1. SS transmits PDSCH via PDCCH DCI format [1\_1] for C\_RNTI to transmit the DL RMC according to Table 7.3.2.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 2. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Tables 7.3.2.4.1-1. Since the UE has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>.
- 4. Set the UE in the Rx beam peak direction found with a 3D EIS scan as performed in Annex K.1.2. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Rx beam selection to complete.
- 5. Perform EIS procedure as stated in Annex K.1.4 to calculate "averaged EIS". At each power level, measure the average throughput for a duration sufficient to achieve statistical significance according to Annex H.2. The downlink power step size shall be no more than 0.2 dB when the RF power level is near the sensitivity level.
- 6. Compare the dB value of the "averaged EIS" value corresponding to the Rx beam peak direction identified in step 5 to the test requirement in table 7.3.2.5-1. If the EIS value is lower or equal to the value in table 7.3.2.5-1, pass the UE. Otherwise fail the UE.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 7.3.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 7.3.2.5 Test requirement

The throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A.2 and A.3 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal as described in Annex A.5) with peak reference sensitivity specified in Tables 7.3.2.5-1 to 7.3.2.5-4. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

Operating		REFSENS (dBm) / Channel bandwidth				
band	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-97.5+TT	-94.5+TT	-91.5+TT	-88.5+TT		
n258	-97.5+TT	-94.5+TT	-91.5+TT	-88.5+TT		
n260	-94.5+TT	-91.5+TT	-88.5+TT	-85.5+TT		
n261	-97.5+TT	-94.5+TT	-91.5+TT	-88.5+TT		

Table 7.3.2.5-1: Reference sensitivity for power class 1

Operating band	REFSENS (dBm) / Channel bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-94.5+TT	-91.5+TT	-88.5+TT	-85.5+TT
n258	-94.5+TT	-91.5+TT	-88.5+TT	-85.5+TT
n260				
n261	-94.5+TT	-91.5+TT	-88.5+TT	-85.5+TT

Table 7.3.2.5-2: Reference sensitivity for power class 2

Table 7.3.2.5-3: Reference sensitivity for power class 3 for single band UE or multi-band UE declaring  $MB_p = 0$  in all FR2 bands

Operating band	REFSENS (dBm) / Channel bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-88.3+TT	-85.3+TT	-82.3+TT	-79.3+TT
n258	-88.3+TT	-85.3+TT	-82.3+TT	-79.3+TT
n259	-84.7+TT	-81.7+TT	-78.7+TT	-75.7+TT
n260	-85.7+TT	-82.7+TT	-79.7+TT	-76.7+TT
n261	-88.3+TT	-85.3+TT	-82.3+TT	-79.3+TT

# Table 7.3.2.5-3a: Reference sensitivity for power class 3 for multi-band UE declaring $MB_p > 0$ in any FR2 band (Rel-15)

Operating band	REFSENS (dBm) / Channel bandwidth (NOTE 1)				
	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-88.3+TT+MBp	-85.3+TT+MBp	-82.3+TT+MBp	-79.3+TT+MBp	
n258	-88.3+TT+MBp	-85.3+TT+MBp	-82.3+TT+MBp	-79.3+TT+MBp	
n260	-85.7+TT+MBp	-82.7+TT+MBp	-79.7+TT+MBp	-76.7+TT+MBp	
n261	-88.3+TT+MBp	-85.3+TT+MBp	-82.3+TT+MBp	-79.3+TT+MBp	
NOTE 1: Refer Table 7.3.2.5-3b for details for MB <sub>p</sub> allowance corresponding to supported FR2 bands set					
NOTE 2: For a Rel-15 UE supporting FR2 bands set not defined in Table 7.3.2.3.3-1a, Table 7.3.2.5-3c applies.					

ID	Supported FR2 bands set	Maximum sum of MB <sub>P,</sub> ∑MB <sub>P</sub> (dB) (Note 3)	Comments		
1	n257, n258	1.3	Maximum 0.75 dB relaxation		
		1.5	allowed for each band		
2	n257, n260	1.0	Maximum 0.75 dB relaxation		
	1207, 1200	1.0	allowed for each band		
3	n258, n260	1.0	Maximum 0.75 dB relaxation		
		1.0	allowed for each band		
4	n258, n261	1.0	Maximum 0.75 dB relaxation		
		1.0	allowed for each band		
5	n260, n261	0.0	No relaxation factor allowed		
6	n257, n258, n260	1.7	Maximum 0.75 dB relaxation		
	11257, 11258, 11200		allowed for each band		
7	n257, n258, n261	1.7	Maximum 0.75 dB relaxation		
		1.7	allowed for each band		
8	n257, n260, n261	0.5	Maximum 0.75 dB relaxation		
		0.5	allowed for each band		
9	n258, n260, n261	1.5	Maximum 0.75 dB relaxation		
		1.5	allowed for each band		
10	n257, n258, n260, n261	1.7	Maximum 0.75 dB relaxation		
		1.7	allowed for each band		
NOTE 1:	MB <sub>p</sub> is the Multiband Relax	xation factor declared by the	e UE for the tested band in table		
	A.4.3.9-2 of TS38.508-2. This declaration shall fulfil the requirements in Table 7.3.2.3.3-				
	1a.				
NOTE 2:	IOTE 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration				
	is compliant				
NOTE 3:	: Max allowed sum of MB <sub>p</sub> over all supported FR2 bands as defined in clause 7.3.2.3.3.				

#### Table 7.3.2.5-3b: Reference sensitivity multi-band relaxation factors for power class 3 (Rel-15)

#### Table 7.3.2.5-3c: Reference sensitivity for power class 3 (Rel-16 and forward)

Operating	REFSENS (dBm) / Channel bandwidth (NOTE 1)					
band	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-88.3+TT+∆МВ <sub>Р,п</sub>	-85.3+TT+ΔМВ <sub>Р,п</sub>	-82.3+TT+∆MB <sub>P,n</sub>	-79.3+TT+∆MB <sub>P,n</sub>		
n258	-88.3+ТТ+∆МВ <sub>Р,п</sub>	-85.3+TT+ΔМВ <sub>Р,п</sub>	-82.3+TT+∆MB <sub>P,n</sub>	-79.3+TT+∆MB <sub>P,n</sub>		
n259	-84.7+ТТ+∆МВ <sub>Р,п</sub>	-81.7+TT+∆МВ <sub>Р,п</sub>	-78.7+TT+∆MB <sub>P,n</sub>	-75.7+TT+∆MB <sub>P,n</sub>		
n260	-85.7+TT+∆МВ <sub>Р,п</sub>	-82.7+TT+∆МВ <sub>Р,п</sub>	-79.7+TT+∆MB <sub>P,n</sub>	-76.7+TT+∆MB <sub>P,n</sub>		
n261	-88.3+TT+∆MB <sub>P,n</sub>	-85.3+TT+∆МВ <sub>Р,п</sub>	-82.3+ТТ+∆МВ <sub>Р,п</sub>	-79.3+TT+∆MB <sub>P,n</sub>		
NOTE 1: Refer	NOTE 1: Refer Table 7.3.2.5-3d for details for $\Delta MB_{P,n}$ allowance corresponding to supported FR2 bands set					

# Table 7.3.2.5-3d: Reference sensitivity multi-band relaxation factors for power class 3 (Rel-16 and<br/>forward)

ID	FR2 bands/set	∆MB <sub>P,n</sub> (dB)	Comments		
1	n257	0.7			
2	n258	0.6			
3	n259	0.5			
4	n260	0.5			
5	n261	0.5			
6	n257, n261	0	$\Delta MB_{P,n}$ relaxation is 0 dB		
7	n260, n261	0	$\Delta MB_{P,n}$ relaxation is 0 dB		
NOTE	NOTE 1: △MB <sub>P,n</sub> is the Multiband Relaxation factor for the tested band. This shall fulfil the requirements in Table 7.3.2.3.3-1b.				

#### Table 7.3.2.5-3e: Test Tolerance (Reference sensitivity for power class 3)

Test Metric	f ≤ 40.8 GHz	
IFF (Quiet Zone size ≤ 30 cm)	2.34 dB	

Operating band	REFSENS (dBm) / Channel bandwidth						
	50 MHz	100 MHz	200 MHz	400 MHz			
n257	-97+TT	-94+TT	-91+TT	-88+TT			
n258	-97+TT	-94+TT	-91+TT	-88+TT			
n260	-95+TT	-92+TT	-89+TT	-86+TT			
n261	-97+TT	-94+TT	-91+TT	-88+TT			

Table 7.3.2.5-4: Reference sensitivity for power class 4

## 7.3.4 EIS spherical coverage

Editor's Note: The following aspects are either missing or not yet determined:

- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2 and 4.
- The test case is incomplete for band n259.

The following aspects of the clause are for future consideration:

- Testing extreme conditions is FFS.

## 7.3.4.1 Test purpose

To verify that the EIS spherical coverage of the UE receiver is acceptable under conditions of low signal level, ideal propagation and no added noise.

## 7.3.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

## 7.3.4.3 Minimum conformance requirements

The reference sensitivity power level REFSENS at a single grid point of the spherical grid is the minimum mean power applied to each one of the UE antenna ports for all UE categories, at which the throughput shall meet or exceed the requirements for the specified reference measurement channel.

The reference measurement channels and throughput criterion shall be as specified in section 7.3.2.3.

For power class 1, the maximum EIS at the 85<sup>th</sup> percentile of the CCDF of EIS measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 7.3.4.3-1 below. The requirement is verified with the test metric of EIS (Link=Spherical coverage grid, Meas=Link angle).

Operating						
band	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-89.5	-86.5	-83.5	-80.5		
n258	-89.5 -86.5 -83.5 -80.4		-80.5			
n260	-86.5 -83.5 -80.5		-77.5			
n261	61 -89.5 -86.5 -83.5		-80.5			
	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.					
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal						
con	conditions as defined in Annex E.2.1.					

For power class 2, the maximum EIS at the 60<sup>th</sup> percentile of the CCDF of EIS measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 7.3.4.3-2 below. The requirement is verified with the test metric of EIS (Link=Spherical coverage grid, Meas=Link angle).

Operating band	EIS at 60 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-83.5	-80.5	-77.5	-74.5		
n258 -83.5		-80.5	-77.5	-74.5		
n261 -83.5 -		-80.5	-77.5	-74.5		
NOTE 1: The tran	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.					
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal						
condition	ns as defined in Anne	ex E.2.1.				

Table 7.3.4.3-2: EIS spherical coverage for power class 2

For power class 3, the maximum EIS at the 50<sup>th</sup> percentile of the CCDF of EIS measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 7.3.4.3-3 below. The requirement is verified with the test metric of EIS (Link=Spherical coverage grid, Meas=Link angle).

For power class 3, the UEs that support operation in multiple FR2 bands, the minimum requirement for EIS spherical coverage in Table 7.3.4.3-3 shall be increased per band, respectively, by the reference sensitivity relaxation parameter  $\sum MB_s$  and  $\Delta MB_{s,n}$  as specified in Table 7.3.2.3.3-1a and 7.3.2.3.3-1b..

Operating band	EIS a	EIS at 50 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth				
	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-77.4	-74.4	-71.4	-68.4		
n258	-77.4	-74.4	-71.4	-68.4		
n259	-71.9	-68.9	-65.9	-62.9		
n260	-73.1	-70.1	-67.1	-64.1		
n261	-77.4	-74.4	-71.4	-68.4		
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4						
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal						
condition	s as defined in Ann	ex E.2.1.				

Table 7.3.4.3-3: EIS spherica	I coverage for power class 3
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For power class 4, the maximum EIS at the 20<sup>th</sup> percentile of the CCDF of EIS measured over the full sphere around the UE is defined as the spherical coverage requirement and is found in Table 7.3.4.3-4 below. The requirement is verified with the test metric of EIS (Link=Spherical coverage grid, Meas=Link angle).

Operating band	EIS a	t 20 <sup>th</sup> %ile CCDF (dBm	bile CCDF (dBm) / Channel bandwidth			
	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-88.0	-85.0	-82.0	-79.0		
n258	-88.0	-85.0	-82.0	-79.0		
n260	-83.0	-80.0	-77.0	-74.0		
n261	-88.0	-85.0	-82.0	-79.0		
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4						
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal						
condition	s as defined in Anne	ex E.2.1.				

The REFSENS requirement shall be met for an uplink transmission using QPSK DFT-s-OFDM waveforms and for uplink transmission bandwidth less than or equal to that specified in Table 7.3.4.3-5.

NR Band / Channel bandwidth / NRB / SCS / Duplex mode							
NR Band	50 MHz	100 MHz	200 MHz	400 MHz	SCS	Duplex Mode	
n257	32	64	128	256	120 kHz	TDD	
n258	32	64	128	256	120 kHz	TDD	
n260	32	64	128	256	120 kHz	TDD	
n261	32	64	128	256	120 kHz	TDD	

 Table 7.3.4.3-5: Uplink configuration for reference sensitivity

Unless given by Table 7.3.4.3-6, the minimum requirements specified in Table 7.3.4.3-1, Table 7.3.4.3-2, Table 7.3.4.3-3 and Tables 7.3.4.3-4 shall be verified with the network signalling value NS\_200 configured.

#### Table 7.3.4.3-6: Network Signalling value for reference sensitivity

NR Band	Network Signalling value
n258	NS_201

For the UE which supports inter-band carrier aggregation, the minimum requirement for reference sensitivity in Table 7.3.4.3-1, Table 7.3.4.3-2, Table 7.3.4.3-3 and Table 7.3.4.3-4 shall be increased by the amount given in  $\Delta R_{IB,c}$  defined in subclause [TBD] for the applicable operating bands.

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3.4.

#### 7.3.4.4 Test description

#### 7.3.4.4.1 Initial conditions

Same initial conditions as in clause 7.3.2.4.1.

#### 7.3.4.4.2 Test procedure

- 1. SS transmits PDSCH via PDCCH DCI format [1\_1] for C\_RNTI to transmit the DL RMC according to Table 7.3.2.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 2. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Tables 7.3.2.4.1-1. Since the UE has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 3. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach  $P_{UMAX}$ .
- 4. Set the UE in the Rx beam peak direction found with a 3D EIS scan as performed in Annex K.1.2. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Rx beam selection to complete.
- 5. Measure UE EIS value for each grid point according to EIS spherical coverage procedure defined in Annex K.1.6, and obtain a Complimentary Cumulative Distribution Function (CCDF) of all EIS dBm values.
- 6. Identify the EIS dBm value corresponding to %-tile (UE power class dependent) value in the applicable test requirement table in section 7.3.4.5.
- 7. Compare the EIS dBm value identified in step 6, to the limit value in the applicable test requirement table in section 7.3.4.5. If the EIS dBm value is lower or equal to the limit value, pass the UE. Otherwise fail the UE.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 7.3.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

## 7.3.4.5 Test requirement

The reference measurement channels and throughput criterion shall be as specified in section 7.3.2.5.

Operating EIS at 85 <sup>th</sup> %ile CCDF (			3m) / Channel bandw	vidth	
band	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-89.5 +TT	-86.5 +TT	-83.5 +TT	-80.5 +TT	
n258	-89.5 +TT	-86.5 +TT	-83.5 +TT	-80.5 +TT	
n260	-86.5 +TT	-83.5 +TT	-80.5 +TT	-77.5 +TT	
n261	-89.5 +TT	-86.5 +TT	-83.5 +TT	-80.5 +TT	
NOTE 1: The	NOTE 1: The transmitter shall be set to P <sub>UMAX</sub> as defined in subclause 6.2.4.				
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal					
conditions as defined in Annex E.2.1.					

Table 7.3.4.5-1: EIS spherical coverage for power class 1

Operating band EIS a		t 60 <sup>th</sup> %ile CCDF (dE	Bm) / Channel band	width
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-83.5 +TT	-80.5 +TT	-77.5 +TT	-74.5 +TT
n258	-83.5 +TT	-80.5 +TT	-77.5 +TT	-74.5 +TT
n261	-83.5 +TT	-80.5 +TT	-77.5 +TT	-74.5 +TT
NOTE 1: The tran	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.			
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal				
conditions as defined in Annex E.2.1.				

# Table 7.3.4.5-3: EIS spherical coverage for power class 3 for single band UE or multi-band UE declaring $MB_s = 0$ in all FR2 bands

Operating band	EIS at 50 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth				
	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-77.4 +TT	-74.4 +TT	-71.4 +TT	-68.4 +TT	
n259	-71.9 +TT	-68.9 +TT	-65.9 +TT	-62.9 +TT	
n258	-77.4 +TT	-74.4 +TT	-71.4 +TT	-68.4 +TT	
n260	-73.1 +TT	-70.1 +TT	-67.1 +TT	-64.1 +TT	
n261	-77.4 +TT	-74.4 +TT	-71.4 +TT	-68.4 +TT	
NOTE 1: The trans	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.				
NOTE 2: The EIS	NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal				
conditions	conditions as defined in Annex E.2.1.				

# Table 7.3.4.5-3a: EIS spherical coverage for power class 3 for multi-band UE declaring $MB_s > 0$ in any FR2 band (Rel-15)

Operating band	EIS at 50 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth (NOTE 3)			
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-77.4 +TT+MBs	-74.4 +TT+MBs	-71.4 +TT+MBs	-68.4 +TT+MBs
n258	-77.4 +TT+MBs	-74.4 +TT+MBs	-71.4 +TT+MBs	-68.4 +TT+MBs
n260	-73.1 +TT+MBs	-70.1 +TT+MBs	-67.1 +TT+MBs	-64.1 +TT+MBs
n261	-77.4 +TT+MBs	-74.4 +TT+MBs	-71.4 +TT+MBs	-68.4 +TT+MBs
NOTE 1: The trans	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.			
	NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal conditions as defined in Annex E.2.1.			
NOTE 3: Refer Table 7.3.4.5-3b for details for MB <sub>s</sub> allowance corresponding to supported FR2 band set combination				
NOTE 4: For a Rel-15 UE supporting FR2 bands set not defined in Table 7.3.2.3.3-1a, Table 7.3.4.5-3c applies.			2.3.3-1a, Table	

ID	Supported FR2 bands set	Maximum sum of MB₅, ∑MB₅ (dB) (Note 3)	Comments		
1	n257, n258	1.25	Maximum 0.75 dB relaxation allowed for each band		
2	n257, n260	0.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
3	n258, n260	0.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
4	n258, n261	1.25	Maximum 0.75 dB relaxation allowed for each band		
5	n260, n261	0.75	No relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
6	n257, n258, n260	1.75	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
7	n257, n258, n261	1.75	Maximum 0.75 dB relaxation allowed for each band		
8	n257, n260, n261	1.25	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
9	n258, n260, n261	1.25	Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands		
10	10       n257, n258, n260, n261       1.75       Maximum 0.4 dB relaxation allowed for n260 and 0.75 dB relaxation allowed for all other bands				
NOTE	NOTE 1: MB <sub>s</sub> is the Multiband Relaxation factor declared by the UE for the tested band in table A.4.3.9-3 of TS38.508- 2. This declaration shall fulfil the requirements in Table 7.3.2.3.3-1a.				
NOTE					
	NOTE 2: All UE supported bands needs to be tested to ensure the multiband relaxation declaration is compliant NOTE 3: Max allowed sum of MB <sub>s</sub> over all supported FR2 bands as defined in clause 7.3.2.3.3.				

### Table 7.3.4.5-3b: EIS spherical coverage multiband relaxation factors for power class 3 (Rel-15)

#### Table 7.3.4.5-3c: EIS spherical coverage for power class 3 (Rel-16 and forward)

Operating band	d EIS at 50 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth (NOTE 3)			IOTE 3)
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-77.4 +TT+∆MB <sub>s,n</sub>	-74.4 +TT+∆MB <sub>s,n</sub>	-71.4 +TT+∆MB <sub>s,n</sub>	-68.4 +TT+ΔMB <sub>s,n</sub>
n258	-77.4 +TT+∆MB <sub>s,n</sub>	-74.4 +TT+∆MB <sub>s,n</sub>	-71.4 +TT+∆MB <sub>s,n</sub>	-68.4 +TT+ΔMB <sub>s,n</sub>
n259	-71.9 +TT+∆MB <sub>s,n</sub>	-68.9 +TT+∆MB <sub>s,n</sub>	-65.9 +TT+∆MB <sub>s,n</sub>	-62.9 +TT+ΔMB <sub>s,n</sub>
n260	-73.1 +TT+∆MB <sub>s,n</sub>	-70.1 +TT+∆MB <sub>s,n</sub>	-67.1 +TT+∆MB <sub>s,n</sub>	-64.1 +TT+∆MB <sub>s,n</sub>
n261	-77.4 +TT+∆MB <sub>s,n</sub>	-74.4 +TT+∆MB <sub>s,n</sub>	-71.4 +TT+∆MB <sub>s,n</sub>	-68.4 +TT+ΔMB <sub>s,n</sub>
NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4.				
NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal conditions as defin		nditions as defined in		
Annex E.2.1.				
NOTE 3: Refer Tabl	e 7.3.4.5-3d for details	for MBs allowance corresp	conding to supported FR2	2 band set combination

# Table 7.3.4.5-3d: EIS spherical coverage multi-band relaxation factors for power class 3 (Rel-16 and<br/>forward)

ID	FR2 bands/set	Comments				
1	n257					
2	n258					
3	n259					
4	n260					
5	n261					
6	n257, n261	$\Delta MB_{s,n}$ relaxation is 0 dB				
7	n260, n261	$\Delta MB_{s,n}$ relaxation is 0 dB				
- 1	NOTE 1: MB <sub>s,n</sub> is the Multiband Relaxation factor for the tested band. This shall fulfil the requirements in Table 7.3.2.3.3-1b.					

## Table 7.3.4.5-3e: Test Tolerance (Reference sensitivity for power class 3)

Test Metric	f ≤ 40.8 GHz	
IFF (Quiet Zone size ≤ 30 cm)	2.21 dB	

Operating band EIS at 20 <sup>th</sup> %ile CCDF (dBm) / Channel bandwidth		width		
	50 MHz	100 MHz	200 MHz	400 MHz
n257	-88.0 +TT	-85.0 +TT	-82.0 +TT	-79.0 +TT
n258	-88.0 +TT	-85.0 +TT	-82.0 +TT	-79.0 +TT
n260	-83.0 +TT	-80.0 +TT	-77.0 +TT	-74.0 +TT
n261	-88.0 +TT	-85.0 +TT	-82.0 +TT	-79.0 +TT
NOTE 1: The trans	NOTE 1: The transmitter shall be set to PUMAX as defined in subclause 6.2.4			
NOTE 2: The EIS s	NOTE 2: The EIS spherical coverage requirements are verified only under normal thermal			
condition	conditions as defined in Annex E.2.1.			

 Table 7.3.4.5-4: EIS spherical coverage for power class 4

## 7.3A Reference sensitivity for CA

#### Editors note:

- Beam peak direction for CA is TBD and cannot be assumed to be the same as single carrier.

## 7.3A.1 General

The reference sensitivity power level REFSENS for both Intra-band non-contiguous CA and Intra-band contiguous CA is defined as the EIS level at the centre of the quiet zone in the RX beam peak direction[(same as that found for single carrier scenario in clause 7.3.2)], at which the throughput shall meet or exceed the requirements for the specified reference measurement channel.

## 7.3A.2 Reference sensitivity power level for CA

## 7.3A.2.0 Minimum Conformance Requirements

#### 7.3A.2.0.1 Intra-band contiguous CA

For each component carrier in the intra-band contiguous carrier aggregation, the throughput in QPSK R = 1/3 shall be  $\geq$  95 % of the maximum throughput of the reference measurement channels as specified in Annex A (with one sided dynamic OCNG Pattern OP.1 TDD for the DL-signal) with peak reference sensitivity values determined from section 7.3.2.3, and relaxation applied to peak reference sensitivity requirement as specified in Table 7.3A.2.0.1-1.

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3A.2.1.

#### Table 7.3A.2.0.1-1: ΔR<sub>IB</sub> EIS Relaxation for CA operation by aggregated channel bandwidth

Aggregated Channel BW 'BW <sub>Channel_CA</sub> ' (MHz)	ΔR <sub>IB</sub> (dB)
BW <sub>Channel_CA</sub> ≤ 800	0.0
800 < BW <sub>Channel_CA</sub> ≤ 1200	0.5

#### 7.3A.2.0.2 Intra-band non-contiguous CA

For each component carrier in the intra-band non-contiguous carrier aggregation, the throughput in QPSK R=1/3 shall be  $\geq$  95 % of the maximum throughput of the reference measurement channels as specified in Annex A (with one sided dynamic OCNG Pattern OP.1 TDD for the DL-signal) with peak reference sensitivity values determined from section 7.3.2.3, and relaxation applied to peak reference sensitivity requirement as specified in Table 7.3A.2.0.2-1.

The cumulative aggregated channel bandwidth is defined as the frequency band from the lowest edge of the lowest CC to the upper edge of the highest CC of all UL and DL configured CCs.

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3A.2.2.

# Table 7.3A.2.0.2-1: $\Delta R_{IB}$ EIS Relaxation for CA operation by cumulative aggregated channel bandwidth

Cumulative Aggregated Channel BW (MHz)	ΔR <sub>IB</sub> (dB)
≤ 800	0.0
[> 800 and ≤ 1400]	[0.5]

## 7.3A.2.1 Reference sensitivity power level for CA (2DL CA)

#### 7.3A.2.1.1 Test purpose

Same test purpose as in clause 7.3.2.1.

#### 7.3A.2.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 2DL CA.

#### 7.3A.2.1.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

7.3A.2.1.4 Test description

#### 7.3A.2.1.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR CA configurations specified in clause 5.5A. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and are shown in Table 7.3A.2.1.4.1-1, Table 7.3A.2.1.4.1-2 and Table 7.3A.2.1.4.1-3. The details of the uplink reference measurement channels (RMCs) are specified in Annex A.2. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

#### Table 7.3A.2.1.4.1-1: Test Configuration Table

Initial Conditions										
Test Environment as specified in TS 38.508-1 [10]       Normal, TL/VL, TL/VH, TH/VL, TH/VH         subclause 4.1       Normal, TL/VL, TL/VH, TH/VL, TH/VH										
Test Frequencies as specified in TS 38.508-1 [10]Low range, High rangesubclause 4.3.1										
	Test CA Bandwidth combination as specified in subclause 5.5A       Maximum aggregated BW (contiguous CA) or Maximum cumulative aggregated BW (non-contiguous CA)									
Test SCS as specified in Table 5.3.5-1 120kHz										
Test Parameters										
Test ID Downlink Configuration Uplink Configuration										
Modulation RB allocation Modulation RB allocation										
1	1 CP-OFDM QPSK Full RB DFT-s-OFDM QPSK REFSENS (NOTE 2, (NOTE 1) NOTE 3)									
NOTE 1: Full RB allocation shall be used per each SCS and component carrier as specified in Table 7.3A.2.1.4.1-2. NOTE 2: REFSENS refers to Table 7.3A.2.1.4.1-3 which defines uplink RB configuration and start RB location for each SCS, channel BW.										
NOTE 3: U	use single carrier UL wr	ien testing reference s	ensitivity power level for CA.	NOTE 3: Use single carrier UL when testing reference sensitivity power level for CA.						

Component Carrier Bandwidth								
<b>50MHz</b> 120 32 32@0								
<b>100MHz</b> 120 66 66@0								
<b>200MHz</b> 120 132 132@0								
<b>400MHz</b> 120 264 264@0								
NOTE 1: CA Bandwidths are checked separately for each NR band, the applicable CA bandwidths are specified in Table 5.3A.4-1.								

Table 7.3A.2.1.4.1-2: Downlink Configuration of each RB allocation

Table 7.3A.2.1.4.1-3: Uplink configuration for reference sensitivity, LCRB@RBstart format
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Operating Band	SCS kHz	50 MHz	100 MHz	200 MHz	400 MHz	Duplex Mode
n257	120	32@0	64@0	128@0	256@0	TDD
n258	120	32@0	64@0	128@0	256@0	TDD
n260	120	32@0	64@0	128@0	256@0	TDD
n261	120	32@0	64@0	128@0	256@0	TDD

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.1, and uplink signals according to Annex G.0, G.1 and G.3.1.
- 4. The UL Reference Measurement channels are set according to Table 7.3A.2.1.4.1-1, Table 7.3A.2.1.4.1-2 and Table 7.3A.2.1.4.1-3.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in State RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 7.3A.2.1.4.3.

#### 7.3A.2.1.4.2 Test Procedure

- 1. Configure SCC according to Annex C.0, C.1, C.2 for all downlink physical channels.
- 2. The SS shall configure SCC as per TS 38.508-1 [10] clause 5.5.1. Message contents are defined in clause 7.3A.2.1.4.3.
- 3. SS activates SCC by sending the activation MAC CE (Refer TS 38.321[28], clauses 5.9, 6.1.3.10). Wait for at least 2 seconds (Refer TS 38.133[25], clause 9.2).
- 4. SS transmits PDSCH via PDCCH DCI format [1\_1] for C\_RNTI to transmit the DL RMC according to Table 7.3A.2.1.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 5. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 7.3A.2.1.4.1-1. Since the UE has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 6. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200msec for the UE to reach P<sub>UMAX</sub>.
- 7. Set the UE in the Rx beam peak direction [(same as that found for single carrier in clause 7.3.2)]. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE Rx beam selection to complete.

- 8. For each component carrier, perform EIS procedure as stated in Annex K.1.4 to calculate "averaged EIS" by changing the power level of the wanted signal with a step size of 0.2dB. For each power step measure the average throughput for a duration sufficient to achieve statistical significance according to Annex H.2.
- 9. For each component carrier, compare the dB value of the "averaged EIS" value corresponding to the Rx beam peak direction (same as that found for single carrier in clause 7.3.2) identified in step 8 to the test requirement in Tables 7.3A.2.1.5-3 to Table 7.3A.2.1.5-7. If the EIS value is lower or equal to the value in Tables 7.3A.2.1.5-3 to Table 7.3A.2.1.5-7, pass the UE. Otherwise fail the UE.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

#### 7.3A.2.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.1.

#### 7.3A.2.1.5 Test requirement

For each component carrier, the throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A.2 and A.3 (with one sided dynamic OCNG Pattern OP.1 FDD/TDD for the DL-signal as described in Annex A.5) with peak reference sensitivity specified in Tables 7.3A.2.1.5-3 to 7.3A.2.1.5-7. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link Angle).

#### Table 7.3A.2.1.5-1: $\Delta R_{IB}$ EIS Relaxation per component carrier for intra-band contiguous CA

Aggregated Channel BW 'BW <sub>Channel_CA</sub> ' (MHz)	ΔR <sub>IB</sub> (dB) / CC
BW <sub>Channel_CA</sub> ≤ 800	0.0
800 < BW <sub>Channel_CA</sub> ≤ 1200	0.5

#### Table 7.3A.2.1.5-2: $\Delta R_{IB}$ EIS Relaxation per component carrier for intra-band non-contiguous CA

Cumulative Aggregated Channel BW (MHz)	ΔR <sub>IB</sub> (dB) / CC
≤ 800	0.0
[> 800 and ≤ 1400]	[0.5]

#### Table 7.3A.2.1.5-3: Reference sensitivity per component carrier for power class 1

Operating	REFSENS (dBm) / CC				
band	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-97.5+TT+ΔR <sub>IB</sub>	-94.5+TT+∆Rı <sub>B</sub>	-91.5+TT+∆R <sub>іВ</sub>	-88.5+TT+∆Rı <sub>B</sub>	
n258	-97.5+TT+ΔR <sub>IB</sub>	-94.5+TT+∆R <sub>IB</sub>	-91.5+TT+∆R <sub>IB</sub>	-88.5+TT+∆R <sub>IB</sub>	
n260	-94.5+TT+ΔR <sub>IB</sub>	-91.5+TT+ΔR <sub>IB</sub>	-88.5+TT+ΔR <sub>IB</sub>	-85.5+TT+ΔR <sub>IB</sub>	
n261	-97.5+TT+ΔR <sub>IB</sub>	-94.5+TT+∆R <sub>IB</sub>	-91.5+TT+∆R <sub>IB</sub>	-88.5+TT+∆R <sub>IB</sub>	

Table 7.3A.2.1.5-4: Reference sensitivity per component carrier for power class 2

Operating band	REFSENS (dBm) / CC				
	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-94.5+TT+∆R <sub>IB</sub>	-91.5+TT+∆R <sub>IB</sub>	-88.5+TT+∆R <sub>IB</sub>	-85.5+TT+∆Rıß	
n258	-94.5+TT+∆R <sub>IB</sub>	-91.5+TT+∆R <sub>IB</sub>	-88.5+TT+∆R <sub>IB</sub>	-85.5+TT+∆Rıß	
n260					
n261	-94.5+TT+∆R <sub>IB</sub>	-91.5+TT+∆R <sub>IB</sub>	-88.5+TT+∆R <sub>IB</sub>	-85.5+TT+∆R <sub>IB</sub>	

#### Table 7.3A.2.1.5-5: Reference sensitivity per component carrier for power class 3

Operating band	REFSENS (dBm) / Channel bandwidth				
	50 MHz	100 MHz	200 MHz	400 MHz	
n257	-88.3+TT+ΔR <sub>IB</sub>	-85.3+TT+∆R <sub>IB</sub>	-82.3+TT+ΔR <sub>IB</sub>	-79.3+TT+∆R <sub>IB</sub>	
n258	-88.3+TT+ΔR <sub>IB</sub>	-85.3+TT+∆R <sub>IB</sub>	-82.3+TT+ΔR <sub>IB</sub>	-79.3+TT+∆Rı <sub>B</sub>	
n260	-85.7+TT+∆R <sub>IB</sub>	-82.7+TT+ΔR <sub>IB</sub>	-79.7+TT+ΔR <sub>IB</sub>	-76.7+TT+ΔR <sub>IB</sub>	
n261	-88.3+TT+ΔR <sub>IB</sub>	-85.3+TT+∆R <sub>IB</sub>	-82.3+TT+ΔR <sub>IB</sub>	-79.3+TT+∆R <sub>IB</sub>	

### Table 7.3A.2.1.5-6a: Test Tolerance per component carrier (Reference sensitivity for power class 3)

Test Metric	f ≤ 40.8 GHz	
IFF (Quiet Zone size ≤ 30 cm)	3.37 dB	

#### Table 7.3A.2.1.5-7: Reference sensitivity per component carrier for power class 4

Operating band	REFSENS (dBm) / Channel bandwidth					
	50 MHz	100 MHz	200 MHz	400 MHz		
n257	-97+TT+∆R <sub>IB</sub>	-94+TT+∆R <sub>IB</sub>	-91+TT+ΔR <sub>IB</sub>	-88+TT+∆R <sub>IB</sub>		
n258	-97+TT+∆R <sub>IB</sub>	-94+TT+∆R <sub>IB</sub>	-91+TT+ΔR <sub>IB</sub>	-88+TT+∆R <sub>IB</sub>		
n260	-95+TT+∆Rıß	-92+TT+ΔR <sub>IB</sub>	-89+TT+ΔR <sub>IB</sub>	-86+TT+∆R <sub>IB</sub>		
n261	-97+TT+∆R <sub>IB</sub>	-94+TT+ΔR <sub>IB</sub>	-91+TT+ΔR <sub>IB</sub>	-88+TT+∆Rı <sub>B</sub>		

## 7.3A.2.2 Reference sensitivity power level for CA (3DL CA)

### 7.3A.2.2.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

#### 7.3A.2.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3DL CA.

### 7.3A.2.2.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

7.3A.2.2.4	Test description
1.0/\	

Same test description as in clause 7.3A.2.1.4.

### 7.3A.2.2.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3A.2.3 Reference sensitivity power level for CA (4DL CA)

7.3A.2.3.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

7.3A.2.3.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 4DL CA.

#### 7.3A.2.3.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

### 7.3A.2.3.4 Test description

Same test description as in clause 7.3A.2.1.4.

#### 7.3A.2.3.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3A.2.4 Reference sensitivity power level for CA (5DL CA)

# 7.3A.2.4.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

# 7.3A.2.4.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 5DL CA.

### 7.3A.2.4.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

### 7.3A.2.4.4 Test description

Same test description as in clause 7.3A.2.1.4.

### 7.3A.2.4.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3A.2.5 Reference sensitivity power level for CA (6DL CA)

### 7.3A.2.5.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

### 7.3A.2.5.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 6DL CA.

## 7.3A.2.5.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

### 7.3A.2.5.4 Test description

Same test description as in clause 7.3A.2.1.4.

### 7.3A.2.5.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3A.2.6 Reference sensitivity power level for CA (7DL CA)

### 7.3A.2.6.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

### 7.3A.2.6.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 7DL CA.

## 7.3A.2.6.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

### 7.3A.2.6.4 Test description

Same test description as in clause 7.3A.2.1.4.

### 7.3A.2.6.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3A.2.7 Reference sensitivity power level for CA (8DL CA)

7.3A.2.7.1 Test purpose

Same test purpose as in clause 7.3A.2.1.1.

### 7.3A.2.7.2 Test applicability

This test case applies to all types of NR UE release 15 and forward that supports FR2 3DL CA.

### 7.3A.2.7.3 Minimum conformance requirements

Same minimum conformance requirements as in clause 7.3A.2.0.

7.3A.2.7.4 Test description

Same test description as in clause 7.3A.2.1.4.

7.3A.2.7.5 Test requirement

For each component carrier, the test requirement is the same as in clause 7.3A.2.1.5.

# 7.3D Reference sensitivity for UL MIMO

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- OTA test procedure for UL MIMO is still under investigation
- 39.905 TP analysis for UL MIMO is pending
- Applicability of Beam peak of single UL is FFS.

The reference sensitivity power level REFSENS for UL MIMO is the EIS level (total component) at the centre of the quiet zone in the RX beam peak direction [TBD], at which the throughput shall meet or exceed the requirements for the specified reference measurement channel.

# 7.3D.1 Reference sensitivity power level for UL MIMO

### 7.3D.1.1 Test purpose

To verify UL MIMO configured UE's ability to receive data with a given average throughput for a specified reference measurement channel, under conditions of low signal level, ideal propagation and no added noise.

A UE unable to meet the throughput requirement under these conditions will decrease the effective coverage area of an g-NodeB.

### 7.3D.1.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

### 7.3D.1.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 7.3.2.3. The requirements shall be met with the UL MIMO configurations specified in Table 7.3D.1.3-1.

Table 7.3D.1.3-1: UL MIMO configuration

Transmission scheme	DCI format	TPMI Index
Codebook based uplink	DCI format 0_1	0

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3D.

7.3D.1.4 Test description

7.3D.1.4.1 Initial conditions

Same initial condition in clause 7.3.2.4.1.

### 7.3D.1.4.2 Test procedure

Same test procedure as in clause 7.3.2.4.2 with the following added to step 2 for UL MIMO configuration:

2.1 The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.

### 7.3D.1.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

### 7.3D.1.5 Test requirement

The test requirement is the same as in clause 7.3.2.5.

# 7.3D.2 EIS spherical coverage for UL MIMO

## 7.3D.2.1 Test purpose

To verify that UL MIMO configured UE's EIS spherical coverage is acceptable under conditions of low signal level, ideal propagation and no added noise.

### 7.3D.2.2 Test applicability

This test case applies to all types of NR UE release 15 and forward supporting UL MIMO.

### 7.3D.2.3 Minimum conformance requirements

For UE configured with UL MIMO, the minimum conformance requirements are defined in clause 7.3.4.3. The requirements shall be met with the UL MIMO configurations specified in Table 7.3D.2.3-1.

#### Table 7.3D.2.3-1: UL MIMO configuration

Transmission scheme	DCI format	TPMI Index
Codebook based uplink	DCI format 0_1	0

The normative reference for this requirement is TS 38.101-2 [3] clause 7.3D.

### 7.3D.2.4 Test description

7.3D.2.4.1	Initial conditions

Same initial condition in clause 7.3.4.4.1.

### 7.3D.2.4.2 Test procedure

Same test procedure as in clause 7.3.4.4.2 with the following added to step 2 for UL MIMO configuration:

2.1 The PDCCH DCI format 0\_1 is specified with the condition 2TX\_UL\_MIMO in 38.508-1 [10] subclause 4.3.6.1.1.2.

### 7.3D.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 ensuring Table 4.6.3-182 with condition 2TX\_UL\_MIMO.

### 7.3D.2.5 Test requirement

The test requirement is the same as in clause 7.3.4.5.

# 7.4 Maximum input level

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement uncertainty is FFS.
- UL power level configuration is TBD.

### 7.4.1 Test purpose

Maximum input level tests the UE's ability to receive data with a given average throughput for a specified reference measurement channel, under conditions of high signal level, ideal propagation and no added noise.

A UE unable to meet the throughput requirement under these conditions will decrease the coverage area near to a g-NodeB.

### 7.4.2 Test applicability

The minimum conformance requirements in this test case are not testable due to maximum input level unachievable in IFF OTA test setup. Other test setups have not been analysed. Thus the test case will not be tested as part of UE conformance testing.

NOTE: As a result TC 7.4 has not been included in the test case applicability table 4.1.2-1, TS 38.522. This does not preclude the test from being used for R&D or other purposes if deemed useful to all types of NR UE release 15 and forward.

#### 7.4.3 Minimum conformance requirements

The maximum input level is defined as the maximum mean power, for which the throughput shall meet or exceed the minimum requirements for the specified reference measurement channel.

The maximum input level is defined as a directional requirement. The requirement is verified in beam locked mode in the direction where peak gain is achieved.

The throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annex A (with one sided dynamic OCNG Pattern OP.1 TDD for the DL-signal as described in Annex A.5.2.1) with parameters specified in Table 7.4.3-1. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link angle).

Rx Parameter	Units	Channel bandwidth			
		50 MHz	100 MHz	200 MHz	400 MHz
Power in transmission bandwidth configuration	dBm	-25 (NOTE 2)			
<ul> <li>NOTE 1: The transmitter shall be set to 4 dB below the PUMAX,f,c as defined in subclause 6.2.4, with uplink configuration specified in Table 7.3.2.3.1-2.</li> <li>NOTE 2: Reference measurement channel is specified in Annex A.3.3: QPSK, R=1/3 variant with one sided dynamic OCNG Pattern as described in Annex A.</li> </ul>					

 Table 7.4.3-1: Maximum input level

The normative reference for this requirement is TS 38.101-2 [3] clause 7.4.

### 7.4.4 Test description

## 7.4.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 7.4.4.1-1. The details of the uplink and downlink reference measurement channels (RMC) are specified in Annexes A.2 and A.3. The details of the OCNG patterns used are specified in Annex A.5. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

### Table 7.4.4.1-1: Test Configuration Table

Initial Conditions					
Test Environment as specifi subclause 4.1	ed in TS 38.508-1 [10]	Normal			
Test Frequencies as specifi subclause 4.3.1	ed in TS 38.508-1 [10]	Mid range			
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1		Lowest, Mid, Highest			
Test SCS as specified in Ta	Test SCS as specified in Table 5.3.5-1		120kHz		
	Test Parameters for	Channel Bandwidths			
Downlink Con	figuration	Uplink Confi	guration		
Modulation	RB allocation	Modulation	RB allocation		
CP-OFDM QPSK	NOTE1	DFT-s-OFDM QPSK	NOTE2		
NOTE 1: The specific configuration of downlink RB allocation is defined in Table 7.3.2.4.1-2. NOTE 2: The specific configuration of uplink RB allocation is defined in Table 7.3.2.4.1-3.					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C, and uplink signals according to AnnexG.
- 4. The DL and UL Reference Measurement channels are set according to Table 7.4.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message content are defined in clause 7.4.4.3.

### 7.4.4.2 Test procedure

- 1. SS transmits PDSCH via PDCCH DCI format [1\_1] for C\_RNTI to transmit the DL RMC according to Table 7.4.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 2. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 7.4.4.1-1. Since the UL has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 3. Set the Downlink signal level for  $\theta$ -polarization to the value as defined in Table 7.4.5-1.
- 4. Set the UE in the Rx beam peak direction found with a 3D EIS scan as performed in Annex K.1.2. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE) for the UE Rx beam selection to complete.
- 5. Send Uplink power control commands to the UE (less or equal to 1dB step size should be used), to ensure that the UE output power is within [TBD] dB of the target power level in Table 7.4.5-1, for at least the duration of the throughput measurement.
- 6. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Rx Only.
- 7. Measure the average throughput for a duration sufficient to achieve statistical significance according to Annex H.2.
- 8. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 9. Repeat steps from 3 to 8, for the downlink signal from  $\varphi$ -polarization.
- 10. Compare the results for both the  $\theta$ -polarization and  $\varphi$ -polarization against the requirement. If either result meets the requirements, pass the UE.
- NOTE: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

### 7.4.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

#### 7.4.5 Test requirement

The throughput measurement derived in test procedure shall be  $\ge 95\%$  of the maximum throughput of the reference measurement channels as specified in Annex A with parameters specified in Tables 7.4.5-1.

Rx Parameter	Units	Channel bandwidth			
		50	100	200	400
		MHz MHz MHz MHz			
Power in Transmission	dBm	-5	1 (NOTE 2,3) for ba	nd n257, n258	and n261
Bandwidth Configuration	UDIII	-59 (NOTE 2,3) for band n260			
NOTE 1: The transmitter shall be set to 4 dB below the PUMAX,f,c as defined in subclause 6.2.4,					ause 6.2.4,
with uplink configuration specified in Table 7.3.2.3.1-2.					
NOTE 2: Reference measurement channel is specified in Annex A.3.3: QPSK, R=1/3 variant with					/3 variant with
one sided dynamic OCNG Pattern as described in Annex A.					
NOTE 3: The test requirements deviate from minimum requirements by 26dB relaxation for 24.25				ation for 24.25	
~ 29.5 GHz and 34 dB relaxation for 37 ~ 40 GHz.					

# 7.4A Maximum input level for CA

FFS

# 7.4D Maximum input level for UL MIMO

FFS

# 7.5 Adjacent channel selectivity

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement Uncertainty is FFS.
- The minimum conformance requirements for Case 2 in this test case are not testable due to maximum input level unachievable in IFF OTA test setup. Other test setups have not been analysed.

### 7.5.1 Test purpose

Adjacent channel selectivity tests the UE's ability to receive data with a given average throughput for a specified reference measurement channel, in the presence of an adjacent channel signal at a given frequency offset from the centre frequency of the assigned channel, under conditions of ideal propagation and no added noise.

### 7.5.2 Test applicability

This test applies to all types of NR UE release 15 and forward.

### 7.5.3 Minimum conformance requirements

Adjacent Channel Selectivity (ACS) is a measure of a receiver's ability to receive a NR signal at its assigned channel frequency in the presence of an adjacent channel signal at a given frequency offset from the centre frequency of the assigned channel. ACS is the ratio of the receive filter attenuation on the assigned channel frequency to the receive filter attenuation on the adjacent channel(s).

The requirement applies at the Radiated Interface Boundary (RIB) when the AoA of the incident wave of the wanted signal and the interfering signal are both from the direction where peak gain is achieved.

The wanted and interfering signals apply to all supported polarizations, under the assumption of polarization match.

The UE shall fulfil the minimum requirement specified in Table 7.5.3-1 for all values of an adjacent channel interferer up to -25 dBm. However, it is not possible to directly measure the ACS, instead the lower and upper range of test parameters are chosen in Table 7.5.3-2 and Table 7.5.3-3 where the throughput shall be  $\geq$  95% of the maximum throughput of the reference measurement channels as specified in Annexes A(with QPSK, R=1/3 and one sided dynamic OCNG Pattern OP.1 TDD for the DL-signal as described in Annex A. The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link angle).

Table 7.5.3-1: Adjacent	channel	selectivity
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		Channel bandwidth				
Rx Parameter	Units	50 MHz	100 MHz	200 MHz	400 MHz	
ACS for band n257, n258, n261	dB	23	23	23	23	
ACS for band n260	dB	22	22	22	22	

Table 7.5.3-2: Test parameters	for adjacent channe	selectivity, Case 1
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Rx Parameter	Units	Channel bandwidth				
		50 MHz	100 MHz	200 MHz	400 MHz	

Power in	dBm						
Transmission		REFSENS + 14 dB					
Bandwidth			REFSENS + 14 dB				
Configuration							
PInterferer for band	dBm	REFSENS	REFSENS	REFSENS	REFSENS		
n257, n258,		+ 35.5 dB	+35.5dB	+35.5dB	+35.5dB		
n261							
PInterferer for band	dBm	REFSENS	REFSENS	REFSENS	REFSENS		
n260		+ 34.5 dB	+34.5dB	+34.5dB	+34.5dB		
BWInterferer	MHz	50	100	200	400		
FInterferer (offset)	MHz	50	100	200	400		
		/	/	/	/		
		-50	-100	-200	-400		
		NOTE 3	NOTE 3	NOTE 3	NOTE 3		
NOTE 1: The int	erferer col	nsists of the Reference	e measurement cha	Innel specified in Annex A	A with one sided dynamic		
		s described in Annex A					
NOTE 2: The RE	FSENS p	ower level is specified	in Table 7.3.2.3-1.	, which are applicable to	different UE power classes.		
NOTE 3: The ab	solute val	ue of the interferer offs	set FInterferer (offset) s	shall be further adjusted t	0		
[FInterferer /SCS] + 0.5)SCS MHz with SCS the sub-carrier spacing of the wanted signal in MHz. Wanted and							
interferer signal have same SCS.							
NOTE 4: The tra	nsmitter s	hall be set to 4 dB bel	ow the PUMAX,f,c as c	lefined in clause 6.2.4, w	ith uplink configuration		
specifie	ed in Table	e 7.3.2.3.1-2.			-		

Table 7.5.3-3: Test parameters for adjacent channel selectivity, Case 2

Rx Parameter	Units		Channel	bandwidth		
		50 MHz	100 MHz	200 MHz	400 MHz	
Power in Transmission Bandwidth Configuration for band n257, n258, n261	dBm	-46.5	-46.5	-46.5	-46.5	
Power in Transmission Bandwidth Configuration for band n260	dBm	-45.5	-45.5	-45.5	-45.5	
PInterferer	dBm			-25		
BWInterferer	MHz	50	100	200	400	
FInterferer (offset)	MHz	50	100	200	400	
		/	/	/	/	
		-50 NOTE 2	-100 NOTE 2	-200 NOTE 2	-400 NOTE 2	
<ul> <li>NOTE 1: The interferer consists of the Reference measurement channel specified in Annex A with one sided dynamic OCNG Pattern TDD as described in Annex A.5.2.1 and set-up according to Annex C.</li> <li>NOTE 2: The absolute value of the interferer offset FInterferer (offset) shall be further adjusted to</li> </ul>						
and int NOTE 3: The tra	([]FInterferer [/SCS] + 0.5)SCS MHz with SCS the sub-carrier spacing of the wanted signal in MHz. Wanted and interferer signal have same SCS.					

The normative reference for this requirement is TS 38.101-2 [3] clause 7.5.

# 7.5.4 Test description

### 7.5.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, and channel bandwidths based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each channel bandwidth and subcarrier spacing, are shown in table 7.5.4.1-1. The details of the uplink and downlink

reference measurement channels (RMCs) are specified in Annexes A. The details of the OCNG patterns used are specified in Annex A. Configurations of PDSCH and PDCCH before measurement are specified in Annex C.2.

	Initial Conditions						
Test Environment as specified in TS 38.508-1 [10] subclause 4.1			Normal				
Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Mid range				
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1		50 MHz, 100 MHz					
Test SCS a	as specified in Table 5.3.5-1		120 kHz				
		Т	est Paramet	ers			
Test ID	Downlink Co	onfiguration		Uplink Con	figuration		
	Modulation	RB allo	ocation	Modulation	RB allocation		
1	CP-OFDM QPSK	NO	TE 1	DFT-s-OFDM QPSK	NOTE 1		
NOTE 1: The specific configuration of each RB allocation is defined in Table 7.3.2.4.1-1.							

Table 7.5.4.1-1: Test Configuration

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.1.4.1 for TE diagram and section A.3.4 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.1, and uplink signals according to Annex G.0, G.1 and G.3.1.
- 4. The UL Reference Measurement channels are set according to Table 7.5.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [10] clause 4.5. Message contents are defined in clause 7.5.4.3.

### 7.5.4.2 Test procedure

- 1. Set the UE in the Rx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.2. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Rx beam selection to complete.
- 2. SS transmits PDSCH via PDCCH DCI format 1\_1 for C\_RNTI to transmit the DL RMC according to Table 7.5.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 3. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 7.5.4.1-1. Since the UL has no payload data to send, the UE transmits uplink MAC padding bits on the UL RMC.
- 4. Send Uplink power control commands to the UE (less or equal to 1dB step size should be used), to ensure that the UE output power is within [TBD] dB of the target power level in Table 7.5.5-2 (Case 1) or Table 7.5.5-3 (Case 2), for at least the duration of the throughput measurement.
- 5. Perform Blocking measurement procedure as stated in Annex K.1.8 using Downlink signal level and Interferer signal level as defined in Table 7.5.5-2 (Case 1). Modulated interferer signal characteristics as defined in Annex D with frequency below the wanted signal.
- 6. Repeat step 5 using an interfering signal frequency above the wanted signal in Case 1.
- 7. Perform Blocking measurement procedure as stated in Annex K.1.8 using Downlink signal level and Interferer signal level as defined in Table 7.5.5-3 (Case 2). Modulated interferer signal characteristics as defined in Annex D with frequency below the wanted signal. Measure throughput for a duration sufficient to achieve statistical significance according to Annex H.2.
- 8. Repeat step 7 using an interfering signal frequency above the wanted signal in Case 2.

9. Repeat for applicable channel bandwidths and operating band combinations in both Case 1 and Case 2.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

# 7.5.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with TRANSFORM\_PRECODER\_ENABLED condition in Table 4.6.3-118 PUSCH-Config.

# 7.5.5 Test requirements

The throughput measurement derived in test procedure shall be  $\geq 95\%$  of the maximum throughput of the reference measurement channels as specified in Annex A, under the conditions specified in Table 7.5.5-2 and also under the conditions specified in Table 7.5.5-3.

		Channel bandwidth				
Rx Parameter	Units	50 MHz	100 MHz	200 MHz	400 MHz	
ACS for band n257, n258, n261	dB	23	23	23	23	
ACS for band n260	dB	22	22	22	22	

### Table 7.5.5-1: Adjacent channel selectivity

Table 7.5.5-2: Test	parameters f	for adjacent	channel	selectivity, Case 1	
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Rx Parameter	Units	Channel bandwidth				
		50 MHz	100 MHz	200 MHz	400 MHz	
Power in	dBm					
Transmission						
Bandwidth			RFI	FSENS + 14 dB		
Configuration						
for band n257,						
n258, n261					555510	
Power in	dBm	REFSENS	REFSEN	REFSENS	REFSENS	
Transmission		+ 14 - 1.8 dB	+ 14 - 4.8 dB	+ 14 dB	+ 14 dB	
Bandwidth		NOTE 4	NOTE 4			
Configuration for						
band n260	al Dura	DEECENO	DEFORMO		DEFOENO	
PInterferer for band	dBm	REFSENS + 35.5 dB	REFSENS +35.5dB	REFSENS +35.5dB	REFSENS +35.5dB	
n257, n258, n261		+ 33.5 UD	+30.00D	NOTE 5	NOTE 5	
11201	dBm	REFSENS	REFSENS	REFSENS	REFSENS	
PInterferer for band	UDIII	+ 34.5 - 1.8 dB	+34.5 - 4.8 dB	+34.5dB	+34.5dB	
n260		NOTE 4	NOTE 4	NOTE 5	NOTE 5	
BWInterferer	MHz	50	100	200	400	
FInterferer (offset)	MHz	50	100	200	400	
		/	/	/	/	
		-50	-100	-200	-400	
		NOTE 3	NOTE 3	NOTE 3	NOTE 3	
NOTE 1: The int	erferer co	nsists of the Reference	e measurement cha	innel specified in Annex A	A with one sided dynamic	
				according to Annex C [].		
		ower level is specified				
				shall be further adjusted t		
			SCS the sub-carrier	spacing of the wanted si	ignal in MHz. Wanted and	
		nave same SCS.				
				and test requirement for	wanted signal and	
		s relaxation to achieve				
		t cannot be tested due			ith uplink configuration	
		e 7.3.2.3.1-2.	UW THE PUMAX, f, c as 0	lefined in clause 6.2.4, w	in upink coniguration	
specific		5 1.0.2.0.1-2.				

Rx Parameter	Units		Channel	bandwidth		
		50 MHz	100 MHz	200 MHz	400 MHz	
Power in Transmission Bandwidth Configuration for band n257, n258, n261	dBm	-46.5	-46.5	-46.5	-46.5	
Power in Transmission Bandwidth Configuration for band n260	dBm	-45.5	-45.5	-45.5	-45.5	
PInterferer	dBm			-25		
BWInterferer	MHz	50	100	200	400	
FInterferer (offset)	MHz	50	100	200	400	
		/	/	/	/	
		-50 NOTE 2	-100 NOTE 2	-200 NOTE 2	-400 NOTE 2	
<ul> <li>NOTE 1: The interferer consists of the Reference measurement channel specified in Annex A with one sided dynamic OCNG Pattern TDD as described in Annex A.5.2.1 and set-up according to Annex C.</li> <li>NOTE 2: The absolute value of the interferer offset FInterferer (offset) shall be further adjusted to</li> </ul>						
[[FinterFerer]/SCS] + 0.5)SCS MHz with SCS the sub-carrier spacing of the wanted signal in MHz. Wanted and interferer signal have same SCS.						
		hall be set to 4 dB below the 7.3.2.3.1-2.	e Pumax,f,c as define	ed in clause 6.2.4, with u	iplink configuration	

# 7.5A Adjacent channel selectivity for CA

FFS

# 7.5D Adjacent channel selectivity for UL MIMO

FFS

# 7.6 Blocking characteristics

The blocking characteristic is a measure of the receiver's ability to receive a wanted signal at its assigned channel frequency in the presence of an unwanted interferer on frequencies other than those of the spurious response or the adjacent channels, without this unwanted input signal causing a degradation of the performance of the receiver beyond a specified limit. The blocking performance shall apply at all frequencies except those at which a spurious response occurs.

The requirement applies at the RIB when the AoA of the incident wave of the wanted signal and the interfering signal are both from the direction where peak gain is achieved.

The wanted and interfering signals apply to all supported polarizations, under the assumption of polarization match.

# 7.6.1 General

FFS

# 7.6.2 In-band blocking

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Measurement uncertainty is FFS.

### 7.6.2.1 Test purpose

In-band blocking is defined for an unwanted interfering signal falling into the UE receive band or into the spectrum equivalent to twice the channel bandwidth below or above the UE receive band at which the relative throughput shall meet or exceed the minimum requirement for the specified measurement channels.

### 7.6.2.2 Test applicability

This test applies to all types of NR UE release 15 and forward.

### 7.6.2.3 Minimum conformance requirements

In-band blocking is defined for an unwanted interfering signal falling into the UE receive band or into the spectrum equivalent to twice the channel bandwidth below or above the UE receive band at which the relative throughput shall meet or exceed the minimum requirement for the specified measurement channels.

The throughput shall be  $\geq 95\%$  of the maximum throughput of the reference measurement channels as specified in Annexes A with one sided dynamic OCNG Pattern for the DL-signal as described in Annex A The requirement is verified with the test metric of EIS (Link=RX beam peak direction, Meas=Link angle).

Rx parameter	Units	Channel bandwidth				
		50 MHz	100 MHz	200 MHz	400 MHz	
Power in Transmission Bandwidth Configuration	dBm	REFSENS + 14dB				
BWInterferer	MHz	50	100	200	400	
P <sub>Interferer</sub> for bands n257, n258, n261	dBm	REFSENS + 35.5 dB	REFSENS + 35.5 dB	REFSENS + 35.5 dB	REFSENS + 35.5 dB	
P <sub>Interferer</sub> for band n260	dBm	REFSENS + 34.5 dB	REFSENS + 34.5 dB	REFSENS + 34.5 dB	REFSENS + 34.5 dB	
Floffset	MHz	≤ 100 & ≥ -100 NOTE 5	≤ 200 & ≥ -200 NOTE 5	≤ 400 & ≥ -400 NOTE 5	≤ 800 & ≥ -800 NOTE 5	
FInterferer	MHz	F <sub>DL_low</sub> + 25	F <sub>DL_low</sub> + 50	F <sub>DL_low</sub> + 100	F <sub>DL_low</sub> + 200	
		to	to	to	to	
		F <sub>DL_high</sub> - 25	F <sub>DL_high</sub> - 50	F <sub>DL_high</sub> - 100	F <sub>DL_high</sub> - 200	
dynami NOTE2: The RE	c OCNG	nsists of the Reference Pattern as described i power level is specified as.	in Annex A and set-u	p according to Ann	ex C.	
		al consists of the refer ynamic OCNG pattern			n Annex A QPSK, R=1/3 cording to Annex C.	
		uency separation betw Interferer signal.	veen the centre of the	e aggregated CA ba	andwidth and the centre	
NOTE 5: The absolute value of the interferer offset Floffset shall be further adjusted to ([  FInterferer  /SCS] + 0.5)SCS([]FInterferer  /SCS] + 0.5)SCS([						
NOTE 6: FInterferen NOTE 7: The tra	r range va nsmitter s	alues for unwanted mo shall be set to 4 dB be ecified in Table 7.3.2.3	dulated interfering s low the PUMAX,f,c as d			

## Table 7.6.2.3-1: In band blocking requirements

The normative reference for this requirement is TS 38.101-2 [10] clause 7.6.2.

### 7.6.2.4 Test description

### 7.6.2.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 7.6.2.4.1-1. The details of the uplink reference measurement channels (RMC) are specified in Annexes A.2 and A.3. Configuration of PDSCH and PDCCH before measurement are specified in Annex C.2. The details of the OCNG patterns used are specified in Annex A.5.

Initial Conditions							
Test Environment as specified in TS 38.508-1 [10]			Normal				
subclause 4.1 Test Frequencies as specified in TS 38.508-1 [10] subclause 4.3.1			Mid range				
Test Channel Bandwidths as specified in TS 38.508-1 [10] subclause 4.3.1		50 MHz, 100 MHz					
Test SCS a	as specified in Table 5.3.5-1		120 kHz				
		Т	est Parame	ters			
Test ID	Downlink Co	onfiguration		Uplink Conf	iguration		
	Modulation	RB allo	ocation	Modulation	RB allocation		
1	CP-OFDM QPSK	NO	TE 1	DFT-s-OFDM QPSK	NOTE 1		
NOTE 1: The specific configuration of each RB allocation is defined in Table 7.3.2.4.1-1.							

### Table 7.6.2.4.1-1: Test Configuration Table

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, in Figure A.3.1.4.1 for TE diagram and section A.3.4 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [10] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1 and C.3.1, and uplink signals according to Annex G.0, G.1 and G.3.1.
- 4. The DL and UL Reference Measurement channels are set according to Table 7.6.2.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity *NR*, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38-508-1 [10] clause 4.5. Message content are defined in clause 7.6.2.4.3.

### 7.6.2.4.2 Test procedure

- 1. Set the UE in the Rx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.2. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Rx beam selection to complete.
- 2. SS transmits PDSCH via PDCCH DCI format 1\_1 for C\_RNTI to transmit the DL RMC according to Table 7.6.2.4.1-1. The SS sends downlink MAC padding bits on the DL RMC.
- 3. SS sends uplink scheduling information for each UL HARQ process via PDCCH DCI format [0\_1] for C\_RNTI to schedule the UL RMC according to Table 7.6.2.4.1-1. Since the UL has no payload and no loopback data to send the UE sends uplink MAC padding bits on the UL RMC.
- 4. Send Uplink power control commands to the UE (less or equal to 1dB step size should be used), to ensure that the UE output power is within [TBD] dB of the target power level in Table 7.6.2.5-1, for at least the duration of the throughput measurement.
- 5. Perform Blocking measurement procedure as stated in Annex K.1.8 using Downlink signal level and Interferer signal level as defined in Table 7.6.2.5-1. Modulated interferer signal characteristics as defined in Annex D. Measure throughput for a duration sufficient to achieve statistical significance according to Annex H.2.
- 6. Repeat steps using interfering signals specified in 7.6.2.5-1. The ranges are covered in steps equal to the interferer bandwidth. Interferer frequencies should be chosen starting with an offset nearest to the centre frequency and sweep outwards towards the band edges. In order to ensure that full range is tested for interferer frequency, run last test steps at frequency equal to F<sub>Interferer</sub> range limit defined at the corresponding band edge.

NOTE 1: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.

### 7.6.2.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6 with TRANSFORM\_PRECODER\_ENABLED condition in Table 4.6.3-118 PUSCH-Config.

## 7.6.2.5 Test requirement

The throughput measurement derived in test procedure shall be  $\ge 95\%$  of the maximum throughput of the reference measurement channels as specified in Annex A with parameters specified in Tables 7.6.2.5-1.

Rx parameter	Units	Channel bandwidth				
		50 MHz	100 MHz	200 MHz	400 MHz	
Power in Transmission Bandwidth Configuration for bands n257, n258, n261	dBm	REFSENS + 14dB				
Power in Transmission Bandwidth Configuration for band n260	dBm	REFSENS + 14 - 1.8 dB NOTE 7	REFSENS + 14 - 4.8 dB NOTE 7	REFSENS + 14 dB	REFSENS + 14 dB	
BWInterferer	MHz	50	100	200	400	
P <sub>Interferer</sub> for bands n257, n258, n261	dBm	REFSENS + 35.5 dB	REFSENS + 35.5 dB	REFSENS + 35.5 dB NOTE 8	REFSENS + 35.5 dB NOTE 8	
P <sub>Interferer</sub> for band n260	dBm	REFSENS + 34.5 - 1.8 dB NOTE 7	REFSENS + 34.5 - 4.8 dB NOTE 7	REFSENS + 34.5 dB NOTE 8	REFSENS + 34.5 dB NOTE 8	
Floffset	MHz	≤ 100 & ≥ -100 NOTE 5	≤ 200 & ≥ -200 NOTE 5	≤ 400 & ≥ -400 NOTE 5	≤ 800 & ≥ -800 NOTE 5	
FInterferer	MHz	F <sub>DL_low</sub> + 25 to F <sub>DL_high</sub> - 25	F <sub>DL_low</sub> + 50 to F <sub>DL_high</sub> - 50	F <sub>DL_low</sub> + 100 to F <sub>DL_high</sub> - 100	F <sub>DL_low</sub> + 200 to F <sub>DL_high</sub> - 200	
<ul> <li>NOTE 1: The interferer consists of the Reference measurement channel specified in Annex A with one sided dynamic OCNG Pattern as described in Annex A and set-up according to Annex C.</li> <li>NOTE2: The REFSENS power level is specified in Section 7.3.2, which are applicable according to different UE power classes.</li> </ul>						
<ul> <li>NOTE 3: The wanted signal consists of the reference measurement channel specified in Annex A QPSK, R=1/3 with one sided dynamic OCNG pattern as described in Annex A and set-up according to Annex C.</li> <li>NOTE 4: Floffset is the frequency separation between the centre of the aggregated CA bandwidth and the centre</li> </ul>						
NOTE 5: The ab 0.5)SC MHz. V	frequency of the Interferer signal. E 5: The absolute value of the interferer offset Floffset shall be further adjusted to ([  Flnterferer  /SCS] + 0.5)SCS([]FInterferer /SCS] + 0.5)SCS MHz with SCS the sub-carrier spacing of the wanted signal in MHz. Wanted and interferer signal have same SCS.					
NOTE 7: Core re interfer	F <sub>Interferer</sub> range values for unwanted modulated interfering signals are interferer centre frequencies. Core requirement cannot be tested due to testability issue and test requirement for wanted signal and interferer includes relaxation to achieve feasible interferer power level. Core requirement cannot be tested due to testability issue.					
NOTE 9: The tra	nsmitter	shall be set to 4 dB below the $P_{UMAX,f,c}$ as defined in clause 6.2.4, with uplink ecified in Table 7.3.2.3.1-2.				

Table 7.6.2.5-1: In band blocking test requirement

7.6.3	Void
7.6A	Blocking characteristics for CA
7.6A.1 FFS	General
<b>7.6A.2</b> FFS	In-band blocking for CA
7.6D <sub>FFS</sub>	Blocking characteristics for UL MIMO
7.7	Void
7.8	Void

# 7.9 Spurious emissions

Editor's note: Following aspects are either missing or not yet determined:

- The testability of this test case is pending further analysis on relaxation of the requirement for band other than n257.

- Measurement Uncertainties and Test Tolerances are FFS for power class 1, 2, and 4.

# 7.9.1 Test purpose

Test verifies the UE's spurious emissions meet the requirements described in clause 7.9.3.

Excess spurious emissions increase the interference to other systems.

# 7.9.2 Test applicability

This test case applies to all types of NR UE release 15 and forward.

# 7.9.3 Minimum conformance requirements

The spurious emissions power is the power of emissions generated or amplified in a receiver. The spurious emissions power level is measured as TRP.

The power of any narrow band CW spurious emission shall not exceed the maximum level specified in Table 7.9.3-1. The requirement is verified in beam locked mode with the test metric of TRP (Link=TX beam peak direction, Meas=TRP grid).

Frequency range	Measurement bandwidth	Maximum level	NOTE	
30MHz ≤ f < 1GHz	100 kHz	-57 dBm	1	
$1GHz \le f \le 2^{nd}$ harmonic of	1 MHz	-47 dBm		
the upper frequency edge of				
the DL operating band in				
GHz				
NOTE 1: Unused PDCCH resources are padded with resource element groups with power level given				
by PDCCH as defined in Annex C.3.1.				

Table 7.9.3-1: General receiver spurious emission requirements

The normative reference for this requirement is TS 38.101-2 [3] clause 7.9.

# 7.9.4 Test description

## 7.9.4.1 Initial conditions

Initial conditions are a set of test configurations the UE needs to be tested in and the steps for the SS to take with the UE to reach the correct measurement state.

The initial test configurations consist of environmental conditions, test frequencies, test channel bandwidths and subcarrier spacing based on NR operating bands specified in Table 5.3.5-1. All of these configurations shall be tested with applicable test parameters for each combination of channel bandwidth and sub-carrier spacing, are shown in table 7.9.4.1-1. The details of the uplink and downlink reference measurement channels (RMC) are specified in Annexes A.2 and A.3. Configuration of PDSCH and PDCCH before measurement are specified in Annex C.2.

Table 7.9.4.1-1: Test Configuration Table

Default Conditions					
	Test Environment as specified in TS				
38.508-1 [	38.508-1 [5] subclause 4.1				
Test Frequ	encies as specified in T	S	Low range, N	Low range, Mid range, High range	
38.508-1 [	5] subclause 4.3.1		_		
Test Chan	Test Channel Bandwidths as specified in		Highest		
TS 38.508-1 [5] subclause 4.3.1		-			
Test SCS a	Test SCS as specified in Table 5.3.5-1		Highest		
	Test Parameters				
Downlink Configura			tion	Uplink Config	guration
Test ID	Mod'n RB		allocation	Mod'n	RB allocation
1	1 N/A		0	N/A	0
NOTE 1: The specific configuration of uplink and downlink are defined in Table 7.3.2.4.1-1.					

- 1. Connection between SS and UE is shown in TS 38.508-1 [10] Annex A, Figure A.3.3.1.1 for TE diagram and Figure A.3.4.1.1 for UE diagram.
- 2. The parameter settings for the cell are set up according to TS 38.508-1 [5] subclause 4.4.3.
- 3. Downlink signals are initially set up according to Annex C.0, C.1, C.2, C.3.1, and uplink signals according to Annex G.0, G.1, G.2, G.3.1.
- 4. The DL and UL Reference Measurement channels are set according to Table 7.9.4.1-1.
- 5. Propagation conditions are set according to Annex B.0.
- 6. Ensure the UE is in state RRC\_CONNECTED with generic procedure parameters Connectivity NR, Connected without release *On*, Test Mode *On* and Test Loop Function *On* according to TS 38.508-1 [5] clause 4.5. Message content are defined in clause 7.5.4.3.

# 7.9.4.2 Test procedure

- 1. Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- If the re-positioning concept is applied, position the device in DUT Orientation 1 if the maximum beam peak direction is within zenith angular range 0°≤θ≤90° for the alignment option selected in step 1; position the device in DUT Orientation 2 (either Options 1 or 2) if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1. If the re-positioning concept is not applied, position the device in DUT Orientation 1.</li>
- 3. Set the UE in the Inband Tx beam peak direction found with a 3D EIRP scan as performed in Annex K.1.1 using the uplink configuration in section 6.2.1.1. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 3) for the UE Tx beam selection to complete.
- 4. SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5. Measure the spurious emissions as per steps outlined below with an exception to the procedure in Annex K if the re-positioning concept is applied (NOTE 4). Step (a) is optional and applicable only if SNR (test requirement level in Table 7.9.5-1 or Table 7.9.5-2 minus offset value minus noise floor of the test system) ≥ 0 dB is guaranteed.
  - (a) Perform coarse TRP measurements to identify spurious emission frequencies and corresponding power level according to the procedures in Annex K, using coarse TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M. The measurement is completed in both polarizations  $\theta$  and  $\phi$  over frequency range and measurement bandwidth according to Table 7.9.5-1 or Table 7.9.5-2. Optionally, a larger and non-constant measurement bandwidth than that of Table 7.9.5-1 or Table 7.9.5-2 may be applied. The measurement period shall capture the active time slots. For each spurious emission frequency with coarse TRP identified to be less than an offset dB from the TRP limit according to Table 7.9.5-1 or Table 7.9.5-2, continue with fine TRP procedures according to step (b).

The offset value shall be the TRP measurement uncertainty at 95% confidence level including the effect of coarse grid measurement uncertainty element, excluding the influence of noise. Different coarse TRP grids and corresponding offset values may be used for different frequencies. The coarse TRP grid and offset values used shall be recorded in the test report.

Grid	Frequency Range	Offset Value			
Constant Density	6 GHz ≤ f < 12.75 GHz	5.25			
	12.75 GHz ≤ f ≤ 23.45GHz	5.21			
	23.45 GHz ≤ f ≤ 40.8GHz	5.49			
	40.8 GHz ≤ f ≤ 66GHz	7.31			
	66 GHz ≤ f ≤ 80GHz	[7.61]			
Constant-Step Size	6 GHz ≤ f < 12.75 GHz	5.38			
	12.75 GHz ≤ f ≤ 23.45GHz	5.34			
	23.45 GHz ≤ f ≤ 40.8GHz	5.62			
	40.8 GHz ≤ f ≤ 66GHz	7.43			
	66 GHz ≤ f ≤ 80GHz	[7.73]			
NOTE 1: These offset values	NOTE 1: These offset values are the upper limit values when fine TRP measurement				
F and when using th	uncertainty of the test system is same as maximum test system uncertainty in Annex F and when using the coarse measurement grid with minimum number of points as specified in Table M.4.5-3.				
NOTE 2: It is allowed to use the	<ol> <li>It is allowed to use the offset values derived based on test system's actual measurement uncertainty budget and denser measurement grid as specified in Table M.4.5.3.</li> </ol>				

(b) Measure fine TRP measurements according to procedures in Annex K, using fine TRP measurement grid selection criteria as per Table M.4.5-3 in Annex M, for each of the spurious emission frequency identified in step (a). Apply a measurement bandwidth according to Table 7.9.5-1 or Table 7.9.5-2.

- 6. SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- NOTE 1: The frequency range defined in Table 7.9.5-1 or Table 7.9.5-2 may be split into ranges. For each range a different test system, e.g. antenna and/or chamber, may be used. To pass the test case all verdicts of the frequency ranges must pass.
- NOTE 2: When switching to DFT-s-OFDM waveform, as specified in the test configuration Table 7.9.4.2-1, send an NR RRCReconfiguration message according to TS 38.508-1 [10] clause 4.6.3 Table 4.6.3-118 PUSCH-Config with TRANSFORM\_PRECODER\_ENABLED condition.
- NOTE 3: The BEAM\_SELECT\_WAIT\_TIME default value is defined in Annex K.1.1.
- NOTE 4: If the (in-band) beam peak is within  $0^{\circ} \le \theta \le 90^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 1 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 2. If the (in-band) beam peak is within  $90^{\circ} < \theta \le 180^{\circ}$ : perform first hemispherical TRP scan ( $0^{\circ} \le \theta \le 90^{\circ}$ ) in DUT Orientation 2 and second hemispherical TRP scan ( $90^{\circ} > \theta \ge 0^{\circ}$ ) in DUT Orientation 1. The DUT with UBF activated needs to be re-positioned during the test.

# 7.9.4.3 Message contents

Message contents are according to TS 38.508-1 [10] subclause 4.6.

# 7.9.5 Test requirement

The measured spurious emissions derived in step 5, shall not exceed the maximum level specified in Table 7.9.5-1 and 7.9.5-2.

Frequency range	Measurement bandwidth	Maximum level	NOTE	
6GHz ≤ f < 20GHz	1 MHz	-47 + 10.2 dBm	1	
$20GHz \le f < 40GHz$	1 MHz	-47 + 17.2 dBm	1	
$\begin{array}{l} 40 GHz \leq f \leq 2^{nd} \text{ harmonic of} \\ \text{the upper frequency edge of} \\ \text{the DL operating band in} \\ GHz \end{array}$	1 MHz	-47 + 33.1 dBm	1	
NOTE 1: Unused PDCCH resources are padded with resource element groups with power level given by PDCCH as defined in Annex C.3.1.				

Table 7.9.5-1: General receiver spurious emission requirements (Band n257)

#### Table 7.9.5-2: General receiver spurious emission requirements (Band n258, n260, n261)

Frequency range	Measurement bandwidth	Maximum level	NOTE	
6GHz ≤ f < 20GHz	1 MHz	-47 + [TBD] dBm	1	
20GHz ≤ f < 40GHz	1 MHz	-47 + [TBD] dBm	1	
$\begin{array}{l} 40GHz \leq f \leq 2^{nd} \text{ harmonic of} \\ \text{the upper frequency edge of} \\ \text{the DL operating band in} \\ GHz \end{array}$	1 MHz	-47 + [TBD] dBm	1	
NOTE 1: Unused PDCCH resources are padded with resource element groups with power level given by PDCCH as defined in Annex C.3.1.				

# 7.10 Void

# Annex A (normative): Measurement channels

A.1	General

TBD

A.2	UL reference measurement channels
/ \.	

A.2.1 General

TBD

A.2.2 Void

# A.2.3 Reference measurement channels for TDD

For UL RMCs defined below, TDD slot pattern defined in Table A.2.3-1 will be used for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, TDD slot patterns defined for reference sensitivity tests in Table A.3.3.1-1 will be used.

		Value		
	Parameter		SCS 120 kHz	
			(µ=3)	
TDD Slot Cont	iguration pattern (Note 1)	DDDSUUUU	7DS8U	
Special Slot C	onfiguration (Note 2)	S=4D+6G+4U	S=12D+2G	
UL-DL	referenceSubcarrierSpacing	60 kHz	120 kHz	
configuration	dl-UL-TransmissionPeriodicity	2 ms	2 ms	
	nrofDownlinkSlots	3	7	
	nrofDownlinkSymbols	4	12	
	nrofUplinkSlot	4	8	
	nrofUplinkSymbols	0	0	
	UL slot numbers	mod(slot index,	mod(slot index,	
OL SIOL HUMbers		40) = {36,,39}	80) = {72,,79}	
NOTE 1: D denotes a slot with all DL symbols; S denotes a slot with a mix of DL, UL and guard				
symbols; U denotes a slot with all UL symbols. The field is for information.				
NOTE 2: D, G, U denote DL, guard and UL symbols, respectively. The field is for information.				

### ETSI453 138 521-2 V16.6.0 (2021-02)

# A.2.3.1 DFT-s-OFDM Pi/2-BPSK

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	pi/2 BPSK	0	1/4	32	16	2	1	132	132
	50-200	60	16	11	pi/2 BPSK	0	1/4	480	16	2	1	2024	2024
	50	60	32	11	pi/2 BPSK	0	1/4	1032	16	2	1	4224	4224
	50	60	64	11	pi/2 BPSK	0	1/4	2024	16	2	1	8448	8448
	100	60	64	11	pi/2 BPSK	0	1/4	2024	16	2	1	8448	8448
	100	60	128	11	pi/2 BPSK	0	1/4	3976	24	2	2	16896	16896
	200	60	128	11	pi/2 BPSK	0	1/4	3976	24	2	2	16896	16896
	200	60	256	11	pi/2 BPSK	0	1/4	7944	24	2	3	33792	33792
Note 1: Note 2: Note 3:	PUSCH mappir 11. DMRS is [T MCS Index is ba If more than one	DM'ed] with Plased on MCS	USCH data. [ Table 6.1.4.1	OM-RS symb -1 defined ir	ools are not cou TS 38.214 [23	unted. 3].						re set to syn	nbols 2, 7,

# Table A.2.3.1-1: Reference Channels for DFT-s-OFDM pi/2-BPSK for 60 kHz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	pi/2 BPSK	0	1/4	32	16	2	1	132	132
	50	120	16	11	pi/2 BPSK	0	1/4	504	16	2	1	2112	2112
	50	120	32	11	pi/2 BPSK	0	1/4	1032	16	2	1	4224	4224
	100	120	32	11	pi/2 BPSK	0	1/4	1032	16	2	1	4224	4224
	100	120	64	11	pi/2 BPSK	0	1/4	2024	16	2	1	8448	8448
	200	120	64	11	pi/2 BPSK	0	1/4	2024	16	2	1	8448	8448
	200	120	128	11	pi/2 BPSK	0	1/4	3976	24	2	2	16896	16896
	400	120	128	11	pi/2 BPSK	0	1/4	3976	24	2	2	16896	16896
	400	120	256	11	pi/2 BPSK	0	1/4	7944	24	2	3	33792	33792
Note 1: Note 2: Note 3: Note 4:	PUSCH mappin 11. DMRS is [TI MCS Index is ba If more than one UL slot numbers measurement p	DM'ed] with Pl ased on MCS e Code Block i s are given by	USCH data. I Table 6.1.4.1 is present, an Table A.2.3-	DM-RS symb -1 defined ir additional C 1 with TDD L	ools are not cou n TS 38.214 [23 CRC sequence JL-DL configur	unted. 3]. of L = 24 I ation spec	Bits is attac	hed to each 3 for the requ	Code Block (ouirements requ	otherwise I uiring at lea	_ = 0 Bit). ast one sub f	rame (1ms)	for the

### Table A.2.3.1-2: Reference Channels for DFT-s-OFDM pi/2-BPSK for 120 kHz SCS

r requirements, OL slot numbers given by the slots satisfying mod(slot index+1, 5) igu ation spe A.3.3.1.

### ETSI455 138 521-2 V16.6.0 (2021-02)

# A.2.3.2 DFT-s-OFDM QPSK

Parameter	Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	QPSK	2	1/6	48	16	2	1	264	132
	50-200	60	16	11	QPSK	2	1/6	808	16	2	1	4048	2024
	50	60	32	11	QPSK	2	1/6	1608	16	2	1	8448	4224
	50	60	64	11	QPSK	2	1/6	3240	16	2	1	16896	8448
	100	60	64	11	QPSK	2	1/6	3240	16	2	1	16896	8448
	100	60	128	11	QPSK	2	1/6	6408	24	2	2	33792	16896
	200	60	128	11	QPSK	2	1/6	6408	24	2	2	33792	16896
	200	60	256	11	QPSK	2	1/6	12808	24	2	4	67584	33792
Note 2: Note 3:	PUSCH mappin 11. DMRS is [TI MCS Index is ba If more than one UL slot number	DM'ed] with Plased on MCS Code Block i	USCH data. I Table 6.1.4.1 is present, an	DM-RS symb -1 defined ir additional C	ools are not cou n TS 38.214 [23 CRC sequence	inted. 5]. of L = 24	Bits is attac	hed to each C	ode Block (ot	herwise L	= 0 Bit).		

# Table A.2.3.2-1: Reference Channels for DFT-s-OFDM QPSK for 60 kHz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

Parameter	Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	QPSK	2	1/6	48	16	2	1	264	132
	50	120	16	11	QPSK	2	1/6	808	16	2	1	4224	2112
	50	120	32	11	QPSK	2	1/6	1608	16	2	1	8448	4224
	100	120	20	11	QPSK	2	1/6	984	16	2	1	5060	2530
	100	120	32	11	QPSK	2	1/6	1608	16	2	1	8448	4224
	100	120	64	11	QPSK	2	1/6	3240	16	2	1	16896	8448
	200	120	64	11	QPSK	2	1/6	3240	16	2	1	16896	8448
	200	120	128	11	QPSK	2	1/6	6408	24	2	2	33792	16896
	400	120	128	11	QPSK	2	1/6	6408	24	2	2	33792	16896
	400	120	256	11	QPSK	2	1/6	12808	24	2	4	67584	33792
Note 2: M Note 3: I	PUSCH mappin 11. DMRS is [TI MCS Index is ba f more than one	DM'ed] with Plased on MCS Code Block i	USCH data. [ Table 6.1.4.1 s present, an	DM-RS syml -1 defined in additional (	ools are not cou n TS 38.214 [23	unted. 3]. of L = 24	Bits is attac	hed to each	Code Block (	otherwise I	_ = 0 Bit).		

## Table A.2.3.2-2: Reference Channels for DFT-s-OFDM QPSK for 120 kHz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

### ETSI4557 138 521-2 V16.6.0 (2021-02)

# A.2.3.3 DFT-s-OFDM 16QAM

Paramete	r Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	16QAM	10	1/3	176	16	2	1	528	132
	50	60	32	11	16QAM	10	1/3	5632	24	1	1	16896	4224
	50	60	64	11	16QAM	10	1/3	11272	24	1	2	33792	8448
	100	60	64	11	16QAM	10	1/3	11272	24	1	2	33792	8448
	100	60	128	11	16QAM	10	1/3	22536	24	1	3	67584	16896
	200	60	128	11	16QAM	10	1/3	22536	24	1	3	67584	16896
	200	60	256	11	16QAM	10	1/3	45096	24	1	6	135168	33792
Note 1: Note 2: Note 3: Note 5:	PUSCH mappir DMRS is [TDM' MCS Index is ba If more than one UL slot numbers measurement p	ed] with PUSC ased on MCS e Code Block i s are given by	CH data. DM- Table 6.1.4.1 is present, an Table A.2.3-	RS symbols -1 defined ir additional C 1 with TDD L	are not counte TS 38.214 [23 RC sequence JL-DL configura	d. 3]. of L = 24 I ation spec	Bits is attac	hed to each Co 3 for the require	ode Block (other	erwise L = ng at least	0 Bit. one sub frar	ne (1ms) for the	9

# Table A.2.3.3-1: Reference Channels for DFT-s-OFDM 16QAM for 60 kHz SCS

A.3.3.1.

### ETSI458 138 521-2 V16.6.0 (2021-02)

Parameter	Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	16QAM	10	1/3	176	16	2	1	528	132
	50	120	16	11	16QAM	10	1/3	2792	16	2	1	8448	2112
	50	120	32	11	16QAM	10	1/3	5632	24	1	1	16896	4224
	100	120	32	11	16QAM	10	1/3	5632	24	1	1	16896	4224
	100	120	64	11	16QAM	10	1/3	11272	24	1	2	33792	8448
	200	120	64	11	16QAM	10	1/3	11272	24	1	2	33792	8448
	200	120	128	11	16QAM	10	1/3	22536	24	1	3	67584	16896
	400	120	128	11	16QAM	10	1/3	22536	24	1	3	67584	16896
	400	120	256	11	16QAM	10	1/3	45096	24	1	6	135168	33792
Note 2:	PUSCH mappi DMRS is [TDM' MCS Index is ba f more than one	ed] with PUSC ased on MCS	CH data. DM- Table 6.1.4.1	RS symbols -1 defined ir	are not counte n TS 38.214 [23	d. 3].		·				e set to symbols 2	r, 7, 11.

### Table A.2.3.3-2: Reference Channels for DFT-s-OFDM 16QAM for 120 kHz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

### ETSI459 138 521-2 V16.6.0 (2021-02)

# A.2.3.4 DFT-s-OFDM 64QAM

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	64QAM	18	1/2	408	16	2	1	792	132
	50	60	32	11	64QAM	18	1/2	12808	24	1	2	25344	4224
	50	60	64	11	64QAM	18	1/2	25608	24	1	4	50688	8448
	100	60	64	11	64QAM	18	1/2	25608	24	1	4	50688	8448
	100	60	128	11	64QAM	18	1/2	51216	24	1	7	101376	16896
	200	60	128	11	64QAM	18	1/2	51216	24	1	7	101376	16896
	200	60	256	11	64QAM	18	1/2	102416	24	1	13	202752	33792
Note 1: Note 2:	PUSCH mappir DMRS is [TDM' MCS Index is b	ed] with PUSC	CH data. DM-	RS symbols	are not counte	d.	additional	DM-RS symbols	, such that the	9 DM-RS p	ositions are	set to symbo	ols 2, 7, 11.
Note 2:							Rite is attac	hed to each Cod	a Black (atha	nwied – (	) Bit		
Note 4:	UL slot numbers	s are given by	Table A.2.3-	1 with TDD l	JL-DL configura	ation speci	ified in A2.3	for the requiren ying mod(slot inc	nents requiring	g at least c	one sub fram		

# Table A.2.3.4-1: Reference Channels for DFT-s-OFDM 64QAM for 60 kHz SCS

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	DFT-s- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	64QAM	18	1/2	408	16	2	1	792	132
	50	120	16	11	64QAM	18	1/2	6400	24	1	1	12672	2112
	50	120	32	11	64QAM	18	1/2	12808	24	1	2	25344	4224
	100	120	32	11	64QAM	18	1/2	12808	24	1	2	25344	4224
	100	120	64	11	64QAM	18	1/2	25608	24	1	4	50688	8448
	200	120	64	11	64QAM	18	1/2	25608	24	1	4	50688	8448
	200	120	128	11	64QAM	18	1/2	51216	24	1	7	101376	16896
	400	120	128	11	64QAM	18	1/2	51216	24	1	7	101376	16896
	400	120	256	11	64QAM	18	1/2	102416	24	1	13	202752	33792
Note 1:	DMRS is [TDM'	ed] with PUSC	CH data. DM-	RS symbols	are not counte	d.	additional	DM-RS symbols	such that the	e DM-RS p	ositions are	set to symbo	ls 2, 7, 11.
Note 2:	MCS Index is ba												
Note 3:								hed to each Cod					
Note 4:								3 for the requiren ying mod(slot ind					

### Table A.2.3.4-2: Reference Channels for DFT-s-OFDM 64QAM for 120 kHz SCS

### ETSI463 138 521-2 V16.6.0 (2021-02)

# A.2.3.5 CP-OFDM QPSK

Parameter	Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	QPSK	2	1/6	48	16	2	1	264	132
	50-200	60	16	11	QPSK	2	1/6	808	16	2	1	4048	2024
	50	60	33	11	QPSK	2	1/6	1672	16	2	1	8712	4356
	50	60	66	11	QPSK	2	1/6	3368	16	2	1	17424	8712
	100	60	66	11	QPSK	2	1/6	3368	16	2	1	17424	8712
	100	60	132	11	QPSK	2	1/6	6536	24	2	2	34848	17424
	200	60	132	11	QPSK	2	1/6	6536	24	2	2	34848	17424
	200	60	264	11	QPSK	2	1/6	13064	24	2	4	69696	34848
Note 2:	PUSCH mappin 11. DMRS is [TI MCS Index is ba f more than one JL slot numbers	DM'ed] with Plased on MCS Code Block i	USCH data. I Table 5.1.3.1 is present, an	DM-RS symb -1 defined ir additional C	ools are not cou n TS 38.214 [23 CRC sequence	unted. 8]. of L = 24 I	Bits is attac	hed to each C	Code Block (ot	herwise L	= 0 Bit)	-	

# Table A.2.3.5-1: Reference Channels for CP-OFDM QPSK for 60 kHz SCS

measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	QPSK	2	1/6	48	16	2	1	264	132
	50	120	16	11	QPSK	2	1/6	808	16	2	1	4224	2112
	50	120	32	11	QPSK	2	1/6	1608	16	2	1	8448	4224
	100	120	33	11	QPSK	2	1/6	1672	16	2	1	8712	4356
	100	120	66	11	QPSK	2	1/6	3368	16	2	1	17424	8712
	200	120	66	11	QPSK	2	1/6	3368	16	2	1	17424	8712
	200	120	132	11	QPSK	2	1/6	6536	24	2	2	34848	17424
	400	120	132	11	QPSK	2	1/6	6536	24	2	2	34848	17424
	400	120	264	11	QPSK	2	1/6	13064	24	2	4	69696	34848
Note 1: Note 2: Note 3: Note 4:	PUSCH mappin 11. DMRS is [TI MCS Index is ba If more than one UL slot numbers measurement p	DM'ed] with Pl ased on MCS e Code Block i s are given by	USCH data. [ Table 5.1.3.1 s present, an Table A.2.3-	DM-RS symb -1 defined ir additional C 1 with TDD L	ools are not cou n TS 38.214 [23 CRC sequence JL-DL configura	unted. 3]. of L = 24 E ation spec	Bits is attac	hed to each 3 for the requ	Code Block ( uirements req	otherwise l uiring at lea	L = 0 Bit) ast one sub f	frame (1ms)	for the

### Table A.2.3.5-2: Reference Channels for CP-OFDM QPSK for 120 kHz SCS

### ETSI463 138 521-2 V16.6.0 (2021-02)

# A.2.3.6 CP-OFDM 16QAM

Paramete	r Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	16QAM	10	1/3	176	16	2	1	528	132
	50	60	33	11	16QAM	10	1/3	5760	24	1	1	17424	4356
	50	60	66	11	16QAM	10	1/3	11528	24	1	2	34848	8712
	100	60	66	11	16QAM	10	1/3	11528	24	1	2	34848	8712
	100	60	132	11	16QAM	10	1/3	23040	24	1	3	69696	17424
	200	60	132	11	16QAM	10	1/3	23040	24	1	3	69696	17424
	200	60	264	11	16QAM	10	1/3	46104	24	1	6	139392	34848
Note 2:	PUSCH mappir DMRS is [TDM' MCS Index is bails If more than one	ed] with PUSC ased on MCS	CH data. DM- Table 5.1.3.1	RS symbols -1 defined ir	are not counte n TS 38.214 [23	d. 3].						e set to symbols 2	, 7, 11.

Table A.2.3.6-1: Reference Channels for CP-OFDM 16QAM for 60 kHz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requirements requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

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Paramete	r Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	16QAM	10	1/3	176	16	2	1	528	132
	50	120	16	11	16QAM	10	1/3	2792	16	2	1	8448	2112
	50	120	32	11	16QAM	10	1/3	5632	24	1	1	16896	4224
	100	120	33	11	16QAM	10	1/3	5760	24	1	1	17424	4356
	100	120	66	11	16QAM	10	1/3	11528	24	1	2	34848	8712
	200	120	66	11	16QAM	10	1/3	11528	24	1	2	34848	8712
	200	120	132	11	16QAM	10	1/3	23040	24	1	3	69696	17424
	400	120	132	11	16QAM	10	1/3	23040	24	1	3	69696	17424
	400	120	264	11	16QAM	10	1/3	46104	24	1	6	139392	34848
Note 1: Note 2: Note 3:	PUSCH mappir DMRS is [TDM' MCS Index is b If more than one	ed] with PUSC ased on MCS	CH data. DM- Table 5.1.3.1	RS symbols -1 defined ir	are not counte TS 38.214 [23	d. 8].		·				set to symbols 2	, 7, 11.

### Table A.2.3.6-2: Reference Channels for CP-OFDM 16QAM for 120 kHz SCS

Note 5: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

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# A.2.3.7 CP-OFDM 64QAM

Paramete	er Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 5)	Total number of bits per slot for UL slots (Note 5)	Total modulated symbols per slot for UL slots (Note 5)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-200	60	1	11	64QAM	19	1/2	408	16	2	1	792	132
	50	60	33	11	64QAM	19	1/2	13064	24	1	2	26136	4356
	50	60	66	11	64QAM	19	1/2	26120	24	1	4	52272	8712
	100	60	66	11	64QAM	19	1/2	26120	24	1	4	52272	8712
	100	60	132	11	64QAM	19	1/2	53288	24	1	7	104544	17424
	200	60	132	11	64QAM	19	1/2	53288	24	1	7	104544	17424
	200	60	264	11	64QAM	19	1/2	106576	24	1	13	209088	34848
Note 1: Note 2: Note 3:	PUSCH mappir 11. DMRS is [T MCS Index is b If more than one	DM'ed] with Plased on MCS	USCH data. [ Table 5.1.3.1	DM-RS syml -1 defined ir	ools are not cou n TS 38.214 [23	unted. 3].					·	are set to sy	mbols 2, 7,

Table A.2.3.7-1: Reference Channels for CP-OFDM 64QAM for 60k Hz SCS

Note 4: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

Parameter	Channel bandwidth	Subcarrier Spacing	Allocated resource blocks	CP- OFDM Symbols per slot (Note 1)	Modulation	MCS Index (Note 2)	Target Coding Rate	Payload size for UL slots (Note 4)	Transport block CRC	LDPC Base Graph	Number of code blocks per slot for UL slots (Note 3, Note 4)	Total number of bits per slot for UL slots (Note 4)	Total modulated symbols per slot for UL slots (Note 4)
Unit	MHz	kHz						Bits	Bits			Bits	
	50-400	120	1	11	64QAM	19	1/2	408	16	2	1	792	132
	50	120	16	11	64QAM	19	1/2	6400	24	1	1	12672	2112
	50	120	32	11	64QAM	19	1/2	12808	24	1	2	25344	4224
	100	120	33	11	64QAM	19	1/2	13064	24	1	2	26136	4356
	100	120	66	11	64QAM	19	1/2	26120	24	1	4	52272	8712
	200	120	66	11	64QAM	19	1/2	26120	24	1	4	52272	8712
	200	120	132	11	64QAM	19	1/2	53288	24	1	7	104544	17424
	400	120	132	11	64QAM	19	1/2	53288	24	1	7	104544	17424
	400	120	264	11	64QAM	19	1/2	106576	24	1	13	209088	34848

## Table A.2.3.7-2: Reference Channels for CP-OFDM 64QAM for 120 kHz SCS

is [TDM'ed] with PUSCH data. DM-RS symbols are not counted.

Note 2: MCS Index is based on MCS Table 5.1.3.1-1 defined in TS 38.214 [23].

Note 3: If more than one Code Block is present, an additional CRC sequence of L = 24 Bits is attached to each Code Block (otherwise L = 0 Bit.

Note 5: UL slot numbers are given by Table A.2.3-1 with TDD UL-DL configuration specified in A2.3 for the requirements requiring at least one sub frame (1ms) for the measurement period. For other requirements, UL slot numbers are given by the slots satisfying mod(slot index+1, 5) = 0 with TDD UL-DL configuration specified in A.3.3.1.

# A.3 DL reference measurement channels

# A.3.1 General

Unless otherwise stated, Tables A.3.3.2-1 and A.3.3.2-2 are applicable for measurements of the Receiver Characteristics (clause 7).

Unless otherwise stated, Tables A.3.3.2-1 and A.3.3.2-2 also apply for the modulated interferer used in Clauses 7.5 and 7.6 with test specific bandwidths.

CSI-RS configuration parameter defined in A.3.1-2 is used for verifying the beam correspondence requirement, 2 slots of CSI-RS shall be provided at each test grid point. The DL channel shall be configured for zero power on all tones except those used by CSI-RS in slots containing CSI-RS for beam refinement, and the DL and UL channel sizes shall be the same during verification.

Para	ameter	Unit	Value				
CORESET frequency doma	ain allocation		Full BW				
CORESET time domain allo	ocation		2 OFDM symbols at the begin of each slot				
PDSCH mapping type			Туре А				
PDSCH start symbol index	(S)		2				
Number of consecutive PD	SCH symbols (L)		12				
PDSCH PRB bundling		PRBs	2				
Dynamic PRB bundling			false				
MCS table for TBS determine	nation		64QAM				
Overhead value for TBS de	termination		0				
First DMRS position for Typ	e A PDSCH mapping		2				
DMRS type			Туре 1				
Number of additional DMRS	3		2				
FDM between DMRS and PDSCH			Disable				
CSI-RS for tracking	First subcarrier index in the PRB used for CSI-RS (k0)		0 for CSI-RS resource 1,2				
	OFDM symbols in the PRB		I0 = 8 for CSI-RS resource 1				
	used for CSI-RS		I0 = 12 for CSI-RS resource 2				
	Number of CSI-RS ports		1 for CSI-RS resource 1,2				
	CDM Type		'No CDM' for CSI-RS resource 1,2				
	Density (ρ)		3 for CSI-RS resource 1,2				
	CSI-RS periodicity	Slots	60 kHz SCS: 80 for CSI-RS resources 1 and 2				
			120 kHz SCS: 160 for CSI-RS resources 1 and 2				
	CSI-RS offset	Slots	60 kHz SCS: 40 for CSI-RS resources 1 and 2				
			120kHz SCS: 80 for CSI-RS resources 1 and 2				
	Frequency Occupation		Start PRB 0				
			Number of PRB = BWP size				
	QCL info		TCI state #0				
PTRS configuration			PTRS is not configured				

### Table A.3.1-1: Test parameters

Resource Type	aperiodic
Resource Set Config	
repetition	on
aperiodicTriggeringOffset	Depending on UE capability
Resource Config	
	30 for resource #0
	31 for resource #1
	32 for resource #2
nzp-CSI-RS-Resourceld	33 for resource #3
hzp-001-100-1080010eld	34 for resource #4
	35 for resource #5
	36 for resource #6
	37 for resource #7
powerControlOffset	0
powerControlOffsetSS	db0
nrofPorts	1
	6 for resource #0
	7 for resource #1
	8 for resource #2
firstOFDMSymbolInTimeDomain	9 for resource #3
	10 for resource #4
	11 for resource #5
	12 for resource #6
	13 for resource #7
cdm-Type	noCDM
density	3
nrofRBs	48 for channel bandwdith≥100MHz 32 for channel bandwidth=50MHz
qcl-info	Type D to SSB

Table A.3.1-2: CSI-RS parameters

### A.3.2 Void

### A.3.3 DL reference measurement channels for TDD

### A.3.3.1 General

#### Table A.3.3.1-1: Additional test parameters for TDD

	Parameter	Va	lue
	Farameter	SCS 60 kHz (µ=2)	SCS 120 kHz (µ=3)
UL-DL	referenceSubcarrierSpacing	60 kHz	120 kHz
configuration	dl-UL-TransmissionPeriodicity	1.25 ms	0.625 ms
	nrofDownlinkSlots	3	3
	nrofDownlinkSymbols	4	10
	nrofUplinkSlot	1	1
	nrofUplinkSymbols	4	2
Number of HARQ	Processes	8	8
K1 value		K1 = 4 if $mod(i,5) = 0$	K1 = 4 if mod(i,5) = 0
		K1 = 3  if  mod(i,5) = 1	K1 = 3  if  mod(i,5) = 1
		K1 = 7  if  mod(i,5) = 2	K1 = 7  if  mod(i,5) = 2
		where i is slot index per frame; i	where i is slot index per frame; i
		= {0,,39}	= {0,,79}

## A.3.3.2 FRC for receiver requirements for QPSK

#### Table A.3.3.2-1: Fixed Reference Channel for Receiver Requirements (SCS 60 kHz, TDD)

Parameter	Unit		Value		
Channel bandwidth	MHz	50	100	200	
Subcarrier spacing configuration $^{\mu}$		2	2	2	
Allocated resource blocks		66	132	264	
Subcarriers per resource block		12	12	12	
Allocated slots per Frame		23	23	23	
MCS index		4	4	4	
Modulation		QPSK	QPSK	QPSK	
Target Coding Rate		1/3	1/3	1/3	
Maximum number of HARQ transmissions		1	1	1	
Information Bit Payload per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79} (NOTE 5)	Bits	N/A	N/A	N/A	
For Slot i, if mod(i, 5) = {0,1,2} for i from {1,,79} (NOTE 6)	Bits	4224	8456	16896	
Transport block CRC	Bits	24	24	24	
LDPC base graph		1	1	1	
Number of Code Blocks per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79} (NOTE 5)	CBs	N/A	N/A	N/A	
For Slot i, if mod(i, 5) = {0,1,2} for i from {1,,79} (NOTE 6)	CBs	1	2	2	
Binary Channel Bits Per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79} (NOTE 5)	Bits	N/A	N/A	N/A	
For Slot i, if mod(i, 5) = {0,1,2} for i from {1,,79} (NOTE 6)	Bits	14256	28512	57024	
Max. Throughput averaged over 1 frame	Mbps	10.138	20.294	40.550	
Note 1:Additional parameters are specified in Table A.3.1-1 and Table A.3.3.1-1.Note 2:If more than one Code Block is present, an additional CRC sequence of L = 24 Bits is attached to each Code Block (otherwise L = 0 Bit).					
Note 3: SS/PBCH block is transmitted in s Note 4: Slot i is slot index per 2 frames	sor o with pen		>		
		RMC for the t	ransmitter ro	quirements	
Note 5: When this DL RMC used together with the UL RMC for the transmitter requirements requiring at least one sub frame (1ms) for the measurement period, Slot i, if mod(i, 8) = $\{3,4,5,6,7\}$ for i from $\{0,,79\}$ together with the TDD UL-DL configuration specified in A2.3.					
Note 6: When this DL RMC used together requiring at least one sub frame (1 8) = {0,1,2} for i from {0,,79} tog in A2.3.	Ims) for the m	neasurement	period, Slot	i, if mod(i,	

Parameter	Unit		Va	lue	
Channel bandwidth	MHz	50 100 200			400
Subcarrier spacing configuration $^{\mu}$		3	3	3	3
Allocated resource blocks		32	66	132	264
Subcarriers per resource block		12	12	12	12
Allocated slots per Frame		47	47	47	47
MCS index		4	4	4	4
Modulation		QPSK	QPSK	QPSK	QPSK
Target Coding Rate		1/3	1/3	1/3	1/3
Maximum number of HARQ transmissions		1	1	1	1
Information Bit Payload per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159} (NOTE 5)	Bits	N/A	N/A	N/A	N/A
For Slot i, if mod(i, 5) = {0,1,2} for i from {1,,159} (NOTE 6)	Bits	2088	4224	8456	16896
Transport block CRC	Bits	16	24	24	24
LDPC base graph		2	1	1	1
Number of Code Blocks per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159} (NOTE 5)	CBs	N/A	N/A	N/A	N/A
For Slot i, if mod(i, 5) = $\{0,1,2\}$ for i from $\{1,,159\}$ (NOTE 6)	CBs	1	1	2	2
Binary Channel Bits Per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159} (NOTE 5)	Bits	N/A	N/A	N/A	N/A
For Slot i, if mod(i, 5) = $\{0,1,2\}$ for i from $\{1,,159\}$ (NOTE 6)	Bits	6912	14256	28512	57024
Max. Throughput averaged over 1 frame	Mbps	10.022	20.275	40.589	81.101
<ul> <li>Note 1: Additional parameters are specified in Table A.3.1-1 and Table A.3.3.1-1.</li> <li>Note 2: If more than one Code Block is present, an additional CRC sequence of L = 24 Bits is attached to each Code Block (otherwise L = 0 Bit).</li> <li>Note 3: SS/PBCH block is transmitted in slot 0 with periodicity 20 ms</li> <li>Note 4: Slot i is slot index per 2 frames</li> <li>Note 5: When this DL RMC used together with the UL RMC for the transmitter requirements requiring at least one sub frame (1ms) for the measurement period, Slot i, if mod(i, 16) = {7,,15} for i from {0,,159} together with the TDD UL-DL configuration specified in A2.3.</li> <li>Note 6: When this DL RMC used together with the UL RMC for the transmitter requirements requiring at least one sub frame (1ms) for the measurement period, Slot i, if mod(i, 16) = {0,,6} for i from {0,,159} together with the TDD UL-DL configuration specified in A2.3.</li> </ul>					

#### Table A.3.3.2-2: Fixed Reference Channel for Receiver Requirements (SCS 120 kHz, TDD)

### A.3.3.3 FRC for receiver requirements for 16QAM

TBD

## A.3.3.4 FRC for receiver requirements for 64QAM

#### Table A.3.3.4-1 Fixed Reference Channel for Receiver Requirements (SCS 60 kHz, TDD)

Parameter	Unit		Value		
Channel bandwidth	MHz	50	100	200	
Subcarrier spacing configuration $\mu$		2	2	2	
Allocated resource blocks		66	132	264	
Subcarriers per resource block		12	12	12	
Allocated slots per Frame		23	23	23	
MCS index		19	19	19	
Modulation		64QAM	64QAM	64QAM	
Target Coding Rate		1/2	1/2	1/2	
Maximum number of HARQ transmissions		1	1	1	
Information Bit Payload per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79}	Bits	N/A	N/A	N/A	
For Slot i, if mod(i, 10) = {0,1,2} for i from {1,,79}	Bits	20496	40976	81976	
Transport block CRC	Bits	24	24	24	
LDPC base graph		1	1	1	
Number of Code Blocks per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79}	CBs	N/A	N/A	N/A	
For Slot i, if mod(i, 10) = {0,1,2} for i from {1,,79}	CBs	3	5	10	
Binary Channel Bits Per Slot					
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,79}	Bits	N/A	N/A	N/A	
For Slot i, if mod(i, 10) = $\{0,1,2\}$ for i from $\{1,,79\}$	Bits	40986	81972	163944	
Max. Throughput averaged over 1 frame	Mbps	49.190	98.343	196.742	
<ul> <li>Note 1: Additional parameters are specified in Table A.3.1-1 and Table A.3.3.1-1.</li> <li>Note 2: If more than one Code Block is present, an additional CRC sequence of L = 24 Bits is attached to each Code Block (otherwise L = 0 Bit).</li> <li>Note 3: SS/PBCH block is transmitted in slot 0 with periodicity 20 ms</li> <li>Note 4: Slot i is slot index per 2 frames</li> <li>Note 5: PTRS is configured on symbols containing PDSCH with 1 port, per 2PRB in</li> </ul>					
frequency domain, per symbol in t assumed to be 6.	ime domain. (	Overhead for	TBS calcula	ition is	

Parameter	Unit		Va	lue			
Channel bandwidth	MHz	50	100	200	400		
Subcarrier spacing configuration $\mu$		3	3	3	3		
Allocated resource blocks		32	66	132	264		
Subcarriers per resource block		12	12	12	12		
Allocated slots per Frame		47	47	47	47		
MCS index		19	19	19	19		
Modulation		64QAM	64QAM	64QAM	64QAM		
Target Coding Rate		1/2	1/2	1/2	1/2		
Maximum number of HARQ transmissions		1	1	1	1		
Information Bit Payload per Slot							
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159}	Bits	N/A	N/A	N/A	N/A		
For Slot i, if mod(i, 5) = {0,1,2} for i from {1,,159}	Bits	9992	20496	40976	81976		
Transport block CRC	Bits	24	24	24	24		
LDPC base graph		1	1	1	1		
Number of Code Blocks per Slot							
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159}	CBs	N/A	N/A	N/A	N/A		
For Slot i, if $mod(i, 5) = \{0, 1, 2\}$ for i from $\{1,, 159\}$	CBs	2	3	5	10		
Binary Channel Bits Per Slot							
For Slots 0 and Slot i, if mod(i, 5) = {3,4} for i from {0,,159}	Bits	N/A	N/A	N/A	N/A		
For Slot i, if $mod(i, 5) = \{0,1,2\}$ for i from $\{1,,159\}$	Bits	19872	40986	81972	163944		
Max. Throughput averaged over 1 frame	Mbps	47.962	98.381	196.685	393.485		
Note 1: Additional parameters are specifie		3.1-1 and Ta	ble A.3.3.1-	1.			
Note 2: If more than one Code Block is present, an additional CRC sequence of $L = 24$ Bits is							
attached to each Code Block (otherwise $L = 0$ Bit).							
Note 4: Slot i is slot index per 2 frames							
Note 5: PTRS is configured on symbols co							
domain, per symbol in time domai	n. Overhead f	or TBS calc	ulation is as	sumed to be	6.		

#### Table A.3.3.4-2 Fixed Reference Channel for Receiver Requirements (SCS 120 kHz, TDD)

## A.4 Void

## A.5 OFDMA Channel Noise Generator (OCNG)

A.5.1 OCNG Patterns for FDD

TBD

## A.5.2 OCNG Patterns for TDD

# A.5.2.1 OCNG TDD pattern 1: Generic OCNG TDD Pattern for all unused REs

#### Table A.5.2.1-1: OP.1 TDD: Generic OCNG TDD Pattern for all unused REs

OCNG Distribution	Control Region	Data Region				
OCNG Parameters	(Core Set)					
Resources allocated	All unused REs (Note 1)	All unused REs (Note 2)				
Structure	PDCCH	PDSCH				
Content	Uncorrelated pseudo random QPSK modulated data	Uncorrelated pseudo random QPSK modulated data				
Transmission scheme for multiple antennas ports transmission	Single Tx port transmission	Spatial multiplexing using any precoding matrix with dimensions same as the precoding matrix for PDSCH				
Subcarrier Spacing	Same as for RMC PDCCH in the active BWP	Same as for RMC PDSCH in the active BWP				
Power Level	Same as for RMC PDCCH	Same as for RMC PDSCH				
<ul> <li>Note 1: All unused REs in the active CORESETS appointed by the search spaces in use.</li> <li>Note 2: Unused available REs refer to REs in PRBs not allocated for any physical channels, CORESETs, synchronization signals or reference signals in channel bandwidth.</li> </ul>						

## Annex B (normative): Propagation conditions

## B.0 No interference

The downlink connection between the System Simulator and the UE is without Additive White Gaussian Noise, and has no fading or multipath effects.

## Annex C (normative): Downlink Physical Channels

## C.0 Downlink signal levels

Editor's Note : Consideration to minimize the required number of additional FR2 link is under discussion

The downlink power settings in Table C.0-1 is used unless otherwise specified in a test case.

SCS			11	Channel Bandwidth			
(kHz)			Unit	50 MHz	100 MHz	200 MHz	400 MHz
60		Number of RBs		66	132	264	N/A
		Channel BW power	dBm	-70	-67	-64	N/A
400		Number of RBs		32	66	132	264
120		Channel BW power	dBm	-70	-67	-64	-61
		SS/PBCH SSS EPRE	dBm/60kHz	[-99]	[-99]	[-99]	[-99]
Note 1:       The channel bandwidth powers are informative, based on [-99]dBm/60kHz SS/PBCH SSS EPRE, then scaled according to the number of RBs and rounded to the nearest integer dBm value. Full RE allocation with no boost or deboost is assumed.         Note 2:       The power level is specified at the centre of quiet zone.							
Note 3:	DL level is applied for any of the Subcarrier Spacing configuration ( $\mu$ ) with the same power spectrum density						
	of [-	-99]dBm/60kHz.					

#### Table C.0-1: Default Downlink power levels for NR

The default downlink signal level uncertainty is +/- TBD dB, for any level specified. If the uncertainty value is critical for the test purpose, a tighter uncertainty is specified for the related test case in Annex F.

For TRP measurement, DL signal may be supplied from RSRP based pathloss compensation link. Downlink signal level using RSRP based pathloss compensation link is specified in Table C.0-2 or Table C.0-3.

## Table C.0-2: Downlink power levels for RSRP based pathloss compensation link for TRP measurement for n257, n258 and n260

SCS	SCS Unit			SCS Channel Bandwidth				Bandwidth	
(kHz)			Unit	50 MHz	100 MHz	200 MHz	400 MHz		
60		Number of RBs		66	132	264	N/A		
60		Channel BW power	dBm	≥ -87	≥ -84	≥ -80	N/A		
120		Number of RBs		32	66	132	264		
120		Channel BW power	dBm	≥ -87	≥ -84	≥ -80	≥ -77		
		SS/PBCH SSS EPRE	dBm/60kHz	≥ -115.5	≥ -115.5	≥ -115.5	≥ -115.5		
<ul> <li>Note 1: The channel bandwidth powers are informative, based on -115.5dBm/60kHz SS/PBCH SSS EPRE, then scaled according to the number of RBs and rounded to the nearest integer dBm value. Full RE allocation with no boost or deboost is assumed.</li> <li>Note 2: The power level is specified at the RSRP reference point as defined in TS 38.215 [24].</li> <li>Note 3: DL level is applied for any of the Subcarrier Spacing configuration ( μ) with the same power spectrum density</li> </ul>									
	of ≥	–115.5 dBm/60kHz.			•				

## Table C.0-3: Downlink power levels for RSRP based pathloss compensation link for TRP measurement for n261

SCS			Channel Bandwidth				
(kHz)			Unit	50 MHz	100 MHz	200 MHz	400 MHz
00		Number of RBs		66	132	264	N/A
60		Channel BW power	dBm	≥ -84	≥ -81	≥ -78	N/A
400		Number of RBs		32	66	132	264
120		Channel BW power	dBm	≥ -84	≥ -81	≥ -78	≥ -75
		SS/PBCH SSS EPRE	dBm/60kHz	≥ -113	≥ -113	≥ -113	≥ -113
<ul> <li>Note 1: The channel bandwidth powers are informative, based on -113dBm/60kHz SS/PBCH SSS EPRE, then scaled according to the number of RBs and rounded to the nearest integer dBm value. Full RE allocation with no boost or deboost is assumed.</li> <li>Note 2: The power level is specified at the RSRP reference point as defined in TS 38.215 [24].</li> <li>Note 3: DL level is applied for any of the Subcarrier Spacing configuration ( μ ) with the same power spectrum density</li> </ul>							
		–113 dBm/60kHz.			,		

## C.1 General

The following clauses describes the downlink Physical Channels that are transmitted during a connection i.e., when measurements are done.

## C.2 Setup

Table C.2-1 describes the downlink Physical Channels that are required for connection set up.

#### Table C.2-1: Downlink Physical Channels required for connection set-up

Physical Channel				
PBCH				
SSS				
PSS				
PDCCH				
PDSCH				
PBCH DMRS				
PDCCH DMRS				
PDSCH DMRS				
CSI-RS				
PTRS				

As common PDSCH and PDCCH configuration parameters the parameters in Table A.3.1-1, C.2-2, C.2-3, and C.2-4 shall be used to bring up the connection setup for FR1 NR cell.

#### Table C.2-2: PDSCH and PDCCH configuration

Parameter	Unit	Value
Number of HARQ processes		8 (TDD)
Aggregation level	CCE	4

#### Table C.2-3: Additional test parameters for TDD for SCS 60 KHz

Parameter		Unit	UL-DL pattern
TDD Slot Configuration pattern (Note 1)			DDSU
Special Slot Configuration (Note 2)			11D+3G+0U
UL-DL configuration	referenceSubcarrierSpacing	kHz	60
(tdd-UL-DL- dl-UL-TransmissionPeriodicity		ms	1
ConfigurationCommon) nrofDownlinkSlots			2

nrofDownlinkSymbols	11			
nrofUplinkSlot	1			
nrofUplinkSymbols	0			
K1 value	K1 = 3 if $mod(i,4) = 0$			
(PDSCH-to-HARQ-timing-indicator)	K1 = 2 if $mod(i,4) = 1$			
	K1 = 5  if  mod(i,4) = 2			
Note 1: D denotes a slot with all DL symbols; S denotes a slot with a mix of DL, UL and guard symbols; U denotes a slot with all UL symbols. The field is for information.				
Note 2: D, G, U denote DL, guard and UL symbols, respectively. The field is for information.				
Note 3: i is the slot index per frame; i = {0,,39}				

Table C.2-4: Additional test parameters for TDD for SCS 120 KHz

Parameter		Unit	UL-DL pattern
TDD Slot Configuration pattern (Note 1) Special Slot Configuration (Note 2)			DDDSU
			10D+2G+2U
UL-DL configuration	referenceSubcarrierSpacing	kHz	120
(tdd-UL-DL-	dl-UL-TransmissionPeriodicity	ms	0.625
ConfigurationCommon)	nrofDownlinkSlots		3
	nrofDownlinkSymbols		10
	nrofUplinkSlot		1
	nrofUplinkSymbols		2
K1 value			K1 = [4] if mod(i,5) = 0
(PDSCH-to-HARQ-timing-indicator)			K1 = [3]  if mod(i,5) = 1 K1 = [2]  if mod(i,5) = 2
			K1 = [6] if $mod(i,5) = 3$
with all UL symbols. The			of DL, UL and guard symbols; U denotes a slot

Note 2: D, G, U denote DL, guard and UL symbols, respectively. The field is for information.

Note 3: i is the slot index per frame;  $i = \{0, ..., 79\}$ 

## C.3 Connection

## C.3.0 Measurement of Transmitter Characteristics

Unless otherwise stated, Table C.3.0-1 is applicable for measurements on the Transmitter Characteristics (clause 6).

Table C.3.0-1: Downlink Physical Channels transmitted during a connection (	(TDD)
	()

Parameter	Unit	Value	
SSS transmit power	W	Test specific	
EPRE ratio of PSS to SSS	dB	0	
EPRE ratio of PBCH to SSS	dB	0	
EPRE ratio of PBCH to PBCH DMRS	dB	0	
EPRE ratio of PDCCH to SSS	dB	0	
EPRE ratio of PDCCH to PDCCH DMRS	dB	0	
EPRE ratio of PDSCH to SSS	dB	0	
EPRE ratio of PDSCH to PDSCH DMRS (Note 1)	dB	-3	
EPRE ratio of CSI-RS to SSS	dB	0	
EPRE ratio of PTRS to PDSCH	dB	Test specific	
EPRE ratio of OCNG DMRS to SSS		0	
EPRE ratio of OCNG to OCNG DMRS (Note 1) dB 0			
Note 1: No boosting is applied to any of the channels except PDSCH DMRS. For			
boosting is applied assuming DMRS Type 1 configuration when DMRS and PDSCH are TDM'ed and only half			
of the DMRS REs are occupied.			
Note 2: Number of DMRS CDM groups without data for PDSCH DMRS configu	2: Number of DMRS CDM groups without data for PDSCH DMRS configuration for OCNG is set to 1.		

## C.3.1 Measurement of Receiver Characteristics

Unless otherwise stated, Table C.3.1-1 is applicable for measurements on the Receiver Characteristics (clause 7). For Adjacent channel selectivity testing, Table C.3.1-2 is applied.

Table C.3.1-1: Downlink Physical (	Channels transmitted during a connection (T	DD)

Parameter	Unit	Value		
SSS transmit power	W	Test specific		
EPRE ratio of PSS to SSS	dB	Ó		
EPRE ratio of PBCH to SSS	dB	0		
EPRE ratio of PBCH to PBCH DMRS	dB	0		
EPRE ratio of PDCCH to SSS	dB	0		
EPRE ratio of PDCCH to PDCCH DMRS	dB	0		
EPRE ratio of PDSCH to SSS	dB	0		
EPRE ratio of PDSCH to PDSCH DMRS (Note 1)	dB	-3		
EPRE ratio of CSI-RS to SSS	dB	0		
EPRE ratio of PTRS to PDSCH	dB	Test specific		
EPRE ratio of OCNG DMRS to SSS	dB	0		
EPRE ratio of OCNG to OCNG DMRS (Note 1)	dB	0		
Note 1: No boosting is applied to any of the channels except P	DSCH DMRS. For PDS	CH DMRS, 3 dB power		
boosting is applied assuming DMRS Type 1 configuration when DMRS and PDSCH are TDM'ed and only half				
of the DMRS REs are occupied.				
Note 2: Number of DMRS CDM groups without data for PDSCH DMRS configuration for OCNG is set to 1.				

Parameter	Unit	Value	Comment
Aggregation level	CCE	4	CBW=50MHz when SCS=120kHz
		0	CBW=50MHz when SCS=60kHz
		8	CBW=100MHz when SCS=120kHz
		16	CBW>100 MHz when SCS=60kHz
		16	CBW>100 MHz when SCS=120kHz

## Annex D (normative): Characteristics of the interfering signal

## D.1 General

Unless otherwise stated, a modulated full bandwidth NR downlink signal, which equals to channel bandwidth of the wanted signal for Single Carrier case is used as interfering signals when RF performance requirements for NR UE receiver are defined. For intra-band contiguous CA case, a modulated NR downlink signal which equals to the aggregated channel bandwidth of the wanted signal is used.

## D.2 Interference signals

Table D.2-1 describes the modulated interferer for different channel bandwidth options.

	Channel bandwidth for Single Carrier			Intra band	
	50 MHz	100 MHz	200 MHz	400 MHz	contiguous CA
BWInterferer	50 MHz	100 MHz	200 MHz	400MHz	BWChannel_CA
RB	NOTE1				
NOTE 1: The RB configured for interfering signal is the same as maximum RB number					
defined in Table 5.3.2-1 for each sub-carrier spacing.					

#### Table D.2-1: Description of modulated NR interferer

## Annex E (normative): Global In-Channel TX-Test

NOTE: Clauses E.2.2 to E.5.9.3 are descriptions, which assume no power ramping adjacent to the measurement period.

## E.1 General

The global in-channel TX test enables the measurement of all relevant parameters that describe the in-channel quality of the output signal of the TX under test in a single measurement process.

The parameters describing the in-channel quality of a transmitter, however, are not necessarily independent. The algorithm chosen for description inside this annex places particular emphasis on the exclusion of all interdependencies among the parameters.

## E.2 Signals and results

### E.2.1 Basic principle

The process is based on the comparison of the actual **output signal of the TX under test**, received by an ideal receiver, with a **reference signal**, that is generated by the measuring equipment and represents an ideal error free received signal. All signals are represented as equivalent (generally complex) baseband signals.

The description below uses numbers as examples. These numbers are taken from TDD with normal CP length and 100 MHz bandwidth with 60 kHz SCS. The application of the text below, however, is not restricted to this frame structure and bandwidth.

### E.2.2 Output signal of the TX under test

The output signal of the TX under test is acquired by the measuring equipment and stored for further processing. It is sampled at a sampling rate of 122.88 Mbps. In the time domain it comprises at least 10 uplink subframes. The measurement period is derived by concatenating the correct number of individual uplink slots until the correct measurement period is reached. The output signal is named z(v). Each slot is modelled as a signal with the following parameters: demodulated data content, carrier frequency, amplitude and phase for each subcarrier, timing, carrier leakage.

#### NOTE 1: TDD

Since the uplink subframes are not continuous, the n slots should be extracted from more than 1 continuous radio frame where

$$n = \begin{cases} 40, \text{ for } 60 \text{ kHz SCS} \\ 80, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

### E.2.3 Reference signal

Two types of reference signal are defined:

The reference signal  $i_1(v)$  is constructed by the measuring equipment according to the relevant TX specifications, using the following parameters: demodulated data content, nominal carrier frequency, nominal amplitude and phase for each

subcarrier, nominal timing, no carrier leakage. It is represented as a sequence of samples at a sampling rate of 122.88 Mbps in the time domain.

The reference signal  $i_2(v)$  is constructed by the measuring equipment according to the relevant TX specifications, using the following parameters: restricted data content: nominal reference symbols, (all modulation symbols for user data symbols are set to 0V), nominal carrier frequency, nominal amplitude and phase for each applicable subcarrier, nominal timing, no carrier leakage. It is represented as a sequence of samples at a sampling rate of 122.88 Mbps in the time domain.

NOTE: The PUCCH is off during the time under test.

### E.2.4 Measurement results

The measurement results, achieved by the global in channel TX test are the following:

- Carrier Frequency error
- EVM (Error Vector Magnitude)
- Carrier leakage
- Unwanted emissions, falling into non allocated resource blocks.
- EVM equalizer spectrum flatness

### E.2.5 Measurement points

The unwanted emission falling into non-allocated RB(s) is calculated directly after the FFT as described below. In contrast to this, the EVM for the allocated RB(s) is calculated after the IDFT for DFT-s-OFDM or after the Tx-Rx chain equalizer for CP-OFDM. The samples after the TX-RX chain equalizer are used to calculate EVM equalizer spectrum flatness. Carrier frequency error and carrier leakage is calculated in the block "RF correction".

In case the parameter 3300 or 3301 is reported from UE via *txDirectCurrentLocation* IE (as defined in TS 38.331 [6]), carrier leakage measurement in the RF correction block shall be omitted. All statements from Annex E.3 onwards shall be read assuming that no carrier leakage has been measured.

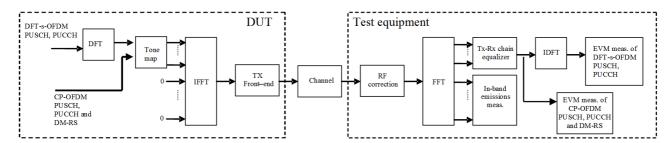


Figure E.2.5-1: EVM measurement points

### E.3 Signal processing

### E.3.1 Pre FFT minimization process

Before applying the pre-FFT minimization process, z(v) and i(v) are portioned into *n* pieces, comprising one slot each, where *n* is as defined in Annex E.2.2.

Each slot is processed separately. Sample timing, Carrier frequency and carrier leakage in z(v) are jointly varied in order to minimise the difference between z(v) and i(v). Best fit (minimum difference) is achieved when the RMS difference value between z(v) and i(v) is an absolute minimum.

The carrier frequency variation and the IQ variation are the measurement results: Carrier Frequency Error and Carrier leakage.

From the acquired samples 10 carrier frequencies can be derived by averaging frequency errors for every 4 or 8 slots for 60 and 120 kHz SCS.

From the acquired samples n carrier frequencies and n carrier leakages can be derived.

- NOTE 1: The minimisation process, to derive carrier leakage and RF error can be supported by Post FFT operations. However the minimisation process defined in the pre FFT domain comprises all acquired samples (i.e. it does not exclude the samples in between the FFT widths and it does not exclude the bandwidth outside the transmission bandwidth configuration
- NOTE 2: The algorithm would allow deriving Carrier Frequency error and Sample Frequency error of the TX under test separately. However there are no requirements for Sample Frequency error. Hence the algorithm models the RF and the sample frequency commonly (not independently). It returns one error and does not distinguish between both.

After this process the samples z(v) are called  $z^0(v)$ .

### E.3.2 Timing of the FFT window

The FFT window length is 2048 samples per OFDM symbol. 14 FFTs (28672 samples) cover less than the acquired number of samples (30720 samples). The position in time for FFT must be determined.

In an ideal signal, the FFT may start at any instant within the cyclic prefix without causing an error. The TX filter, however, reduces the window. The EVM requirements shall be met within a window W<CP. There are three different instants for FFT:

Centre of the reduced window, called  $\Delta \tilde{c}$ ,  $\Delta \tilde{c}$  –W/2 and  $\Delta \tilde{c}$  +W/2.

The timing of the measured signal is determined in the pre FFT domain as follows, using  $z^{0}(v)$  and  $i_{2}(v)$ :

- 1. The measured signal is delay spread by the TX filter. Hence the distinct boarders between the OFDM symbols and between Data and CP are also spread and the timing is not obvious.
- 2. In the Reference Signal  $i_2(v)$  the timing is known.
- 3. Correlation between (1.) and (2.) will result in a correlation peak. The meaning of the correlation peak is approx. the "impulse response" of the TX filter. The meaning of "impulse response" assumes that the autocorrelation of the reference signal  $i_2(v)$  is a Dirac peak and that the correlation between the reference signal  $i_2(v)$  and the data in the measured signal is 0. The correlation peak, (the highest, or in case of more than one, the earliest) indicates the timing in the measured signal.

From the acquired samples, *n* timings can be derived.

For all calculations, except EVM, the number of samples in  $z^0(v)$  is reduced to 14 blocks of samples, comprising 2048 samples (FFT width) and starting with  $\Delta \tilde{c}$  in each OFDM symbol including the demodulation reference signal.

For the EVM calculation the output signal under test is reduced to 28 blocks of samples, comprising 2048 samples (FFT width) and starting with  $\Delta \tilde{c}$  –W/2 and  $\Delta \tilde{c}$  +W/2 in each OFDM symbol including the demodulation reference signal.

The number of samples, used for FFT is reduced compared to  $z^{0}(v)$ . This subset of samples is called z'(v).

The timing of the centre  $\Delta \tilde{c}$  with respect to the different CP length in a slot is as follows: (TDD, normal CP length)

 $\Delta \tilde{c}$  is on T<sub>f</sub>=72 (=CP/2) within the CP of length 144 FFT samples (in OFDM symbols except 0 and 28 (=7 · 2<sup>k</sup>), where symbol 0 is the first symbol of each subframe) for channel bandwidth of 100 MHz and SCS = 60 kHz.

 $\Delta \tilde{c}$  is on T<sub>f</sub>=136 (=208-72) within the CP of length 208 FFT samples (in OFDM symbol 0 and 28 (=7 · 2<sup>\*</sup>), where symbol 0 is the first symbol of each subframe) for channel bandwidth of 100 MHz and SCS = 60 kHz.

### E.3.3 Post FFT equalisation

Perform 14 FFTs on z'(v), one for each OFDM symbol in a slot using the timing  $\Delta \tilde{c}$ , including the demodulation reference symbol. The result is an array of samples, 14 in the time axis t times 2048 in the frequency axis f. The samples represent the data symbols (in OFDM-symbol 0,1,3,4,5,6,8,9,10,12,13 in each slot) and demodulation reference symbols (OFDM symbol 2, 7, 11 in each slot) in the allocated RBs and inband emissions in the non allocated RBs within the transmission BW.

Only the allocated resource blocks in the frequency domain are used for equalisation.

The nominal demodulation reference symbols and nominal data symbols are used to equalize the measured data symbols. (Location for equalization see Figure E.2.5-1)

NOTE: The nomenclature inside this note is local and not valid outside.

The nominal data symbols are created by a demodulation process. The location to gain the demodulated data symbols is "EVM" in Figure E.2.5-1. For CP-OFDM, the process described in Annex E.5 can be applied. A demodulation process as follows is recommended for DFT-s-OFDM:

- 1. Equalize the measured data symbols using the reference symbols for equalisation. Result: Equalized data symbols
- 2. Only for DFT-s-OFDM, iDFT transform the equalized data symbols: Result: Equalized data symbols
- 3. Decide for the nearest constellation point: Result: Nominal data symbols
- 4. Only for DFT-s-OFDM, DFT transform the nominal data symbols: Result: Nominal data symbols

At this stage we have an array of <u>M</u>easured data-<u>S</u>ymbols and reference-<u>S</u>ymbols (MS(f,t))

versus an array of Nominal data-Symbols and reference Symbols (NS(f,t))

(complex, the arrays comprise 11 data symbols and 3 demodulation reference symbol in the time axis and the number of allocated subcarriers in the frequency axis.)

MS(f,t) and NS(f,t) are processed with a least square (LS) estimator, to derive one equalizer coefficient per time slot and per allocated subcarrier. EC(f) is defined as

$$EC(f) = \frac{\sum_{t=0}^{13} NS(f,t)^* NS(f,t)}{\sum_{t=0}^{13} NS(f,t)^* MS(f,t)}$$

With \* denoting complex conjugation.

EC(f) are used to equalize the DFT-coded data symbols. The measured DFT-coded data and the references symbols are equalized by:

$$Z'(f,t) = MS(f,t) \cdot EC(f)$$

With · denoting multiplication.

Z'(f,t), restricted to the data symbol (excluding t=2,7,11) is used to calculate EVM, as described in E.4.1.

EC(f) is used in E.4.4 to calculate EVM equalizer spectral flatness.

NOTE: The post FFT minimisation process is done over 14 symbols (11 DFT-coded data symbols and 3 reference symbols).

The samples of the non allocated resource blocks within the transmission bandwidth configuration in the post FFT domain are called Y(f,t) (f covering the non allocated subcarriers within the transmission bandwidth configuration, t covering the OFDM symbols during 1 slot).

## E.4 Derivation of the results

### E.4.1 EVM

For EVM create two sets of Z'(f,t)., according to the timing " $\Delta \tilde{c} - W/2$  and  $\Delta \tilde{c} + W/2$ " using the equalizer coefficients from E.3.3.

Perform the iDFTs on Z'(f,t) in the case of DFT-s-OFDM waveform. The IDFT-decoding preserves the meaning of t but transforms the variable f (representing the allocated sub carriers) into another variable g, covering the same count and representing the demodulated symbols. The samples in the post IDFT domain are called iZ'(g, t). The equivalent ideal samples are called iI(g,t). Those samples of Z'(f,t), carrying the reference symbols (=symbol 2,7,11) are not iDFT processed.

The EVM is the difference between the ideal waveform and the measured and equalized waveform for the allocated RB(s)

$$EVM = \sqrt{\frac{\sum_{t \in T} \sum_{g \in G} \left| iZ \right|^{\prime} \left(g, t\right) - iI\left(g, t\right)^{2}}{\left|G\right| \cdot \left|T\right| \cdot P_{0}}},$$

where

t covers the count of demodulated symbols with the considered modulation scheme being active within the measurement period, (i.e. symbol 0,1,3,4,5,6,8,9,10,12,13 in each slot,  $\rightarrow$ |T|=11)

g covers the count of demodulated symbols with the considered modulation scheme being active within the allocated bandwidth. ( $|G|=12*L_{CRBs}$  (with  $L_{CRBs}$ : number of allocated resource blocks)).

iZ'(g,t) are the samples of the signal evaluated for the EVM.

iI(g,t) is the ideal signal reconstructed by the measurement equipment, and

 $P_0$  is the average power of the ideal signal. For normalized modulation symbols  $P_0$  is equal to 1.

From the acquired samples 2n EVM values can be derived, n values for the timing  $\Delta \tilde{c}$  -W/2 and n values for the timing  $\Delta \tilde{c}$  +W/2

### E.4.2 Averaged EVM

EVM is averaged over all basic EVM measurements.

The averaging comprises n UL slots

$$\overline{EVM} = \sqrt{\frac{1}{n} \sum_{i=1}^{n} EVM_{i}^{2}}$$

where

$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}$$

for PUCCH, PUSCH.

The averaging is done separately for timing  $\Delta \tilde{c}$  -W/2 and  $\Delta \tilde{c}$  +W/2 leading to  $EVM_1$  and  $EVM_h$ 

 $EVM_{\text{final}} = \max(\overline{\text{EVM}}_1, \overline{\text{EVM}}_h)$  is compared against the test requirements.

### E.4.3 In-band emissions measurement

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks.

Explanatory Note:

The inband emission measurement is only meaningful with allocated RB(s) next to non-allocated RB. The allocated RB(s) are necessary but not under test. The non allocated RBs are under test. The RB allocation for this test is as follows: The allocated RB(s) are at one end of the channel BW, leaving the other end unallocated. The number of allocated RB(s) is smaller than half of the number of RBs, available in the channel BW. This means that the vicinity of the carrier in the centre is unallocated.

There are 3 types of inband emissions:

- 1. General
- 2. IQ image
- 3. Carrier leakage

Carrier leakage are inband emissions next to the carrier.

IQ image are inband emissions symmetrically (with respect to the carrier) on the other side of the allocated RBs.

General are applied to all unallocated RBs.

For each evaluated RB, the minimum requirement is calculated as the higher of  $P_{RB}$  - 30 dB and the power sum of all limit values (General, IQ Image or Carrier leakage) that apply.

In specific the following combinations:

- Power (General)
- Power (General + Carrier leakage)
- Power (General + IQ Image)

1 and 2 is expressed in terms of power in one non allocated RB under test, normalized to the average power of an allocated RB (unit dB).

3 is expressed in terms of power in one non allocated RB, normalized to the power of all allocated RBs. (unit dBc).

This is the reason for two formulas Emissions relative.

Create one set of Y(t,f) per slot according to the timing " $\Delta \tilde{c}$ "

For the non-allocated RBs below the in-band emissions are calculated as follows

$$Emissions_{absolute}(\Delta_{RB}) = \begin{cases} \frac{1}{|T_s|} \sum_{t \in T_s} \sum_{\substack{max(f_{\min}, (c_t+12:\Delta_{RB}+11)^*\Delta f \\ max(f_{\min}, (c_t+12:\Delta_{RB}+\Delta f)) \\ min(f_{\max}, (c_h+12:\Delta_{RB}+\Delta f)) \\ \frac{1}{|T_s|} \sum_{t \in T_s} \sum_{\substack{c_h+(12:\Delta_{RB}-11)^*\Delta f \\ c_h+(12:\Delta_{RB}-11)^*\Delta f }} |Y(t, f)|^2, \Delta_{RB} < 0 \end{cases}$$

where

the upper formula represents the in band emissions below the allocated frequency block and the lower one the in band emissions above the allocated frequency block.

 $T_s$  is a set of  $|T_s|$  DFT-s-OFDM symbols with the considered modulation scheme being active within the measurement period,

 $\Delta_{RB}$  is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g.  $\Delta_{RB} = 1$  for the first upper or  $\Delta_{RB} = -1$  for the first lower adjacent RB),

 $f_{\min}$  and  $f_{\max}$  are the lower and upper edge of the UL transmission BW configuration,

 $c_l$  and  $c_h$  are the lower and upper edge of the allocated BW,

 $\Delta f$  is the SCS, and

Y(t, f) is the frequency domain signal evaluated for in-band emissions as defined in clause E.3.3

The allocated RB power per RB and the total allocated RB power are given by:

$$P_{RB} = \frac{1}{|T_s| \cdot L_{CRBs}} \sum_{t \in T_s} \sum_{t \in T_s} \sum_{c_1}^{c_1 + (12 \cdot L_{CRBs} - 1) \cdot \Delta f} |MS(t, f)|^2 [dBm/(12\Delta f)]$$
$$P_{All-RBs} = \frac{1}{|T_s|} \sum_{t \in T_s} \sum_{c_1}^{c_1 + (12 \cdot L_{CRBs} - 1)^* \Delta f} |MS(t, f)|^2 [dBm]$$

The relative in-band emissions, applicable for General and IQ image, are given by:

$$Emissions_{relative}(\Delta_{RB}) = 10 \cdot \log_{10} \left( \frac{Emissions_{absolute}(\Delta_{RB})}{\frac{1}{|T_S| \cdot L_{CRBS}} \sum_{c_l} \sum_{c_l} \sum_{c_l} \sum_{c_l} \sum_{c_l} ||\mathbf{MS}(t,f)|^2} \right) [dB] = Emissions_{absolute}(\Delta_{RB}) [dBm/12\Delta f] - P_{RB} [dBm/12\Delta f]$$

where

 $L_{CRBs}$  is the number of allocated resource blocks,

and

MS(t, f) is the frequency domain samples for the allocated bandwidth, as defined in clause E.3.3.

The relative in-band emissions, applicable for carrier leakage, is given by:

$$Emissions_{relative} = 10 \cdot \log_{10} \left( \frac{Emissions_{absolute}(RBnextDC)}{\frac{1}{|T_s|} \sum_{t \in T_s} \sum_{c_l}^{c_l + (12 \cdot L_{CRBs} - 1) \cdot \Delta f} |MS(t, f)|^2} \right) [dBc]$$
  
= Emissions\_{absolute}(RBnextDC)[dBm/12\Delta f] - P\_{All RBs}[dBm]

where RBnextDC means: Resource Block next to the carrier.

This can be one RB or one pair of RBs, depending whether the DC carrier is inside an RB or in-between two RBs.

Although an exclusion period may be applicable in the time domain, when evaluating EVM, the inband emissions measurement interval is defined over one complete slot in the time domain.

From the acquired samples *n* functions for general in band emissions and IQ image inband emissions can be derived. n values or n pairs of carrier leakage inband emissions can be derived. They are compared against different limits.

The in-band emissions are averaged over the *n* samples (equivalent to 10 UL subframes):

$$\overline{Emissions}_{absolute}(\Delta_{RB}) = \frac{1}{n} \sum_{i=1}^{n} Emissions_{absolute,i}(\Delta_{RB})$$

$$\overline{Emissions}_{relative}(\Delta_{RB}) = 10 * \log_{10} \left(\frac{1}{n} \sum_{i=1}^{n} 10^{Emissions}_{relative,i}(\Delta_{RB})/10\right) \quad [dB]$$

$$\overline{Emissions}_{relative} = 10 * \log_{10} \left(\frac{1}{n} \sum_{i=1}^{n} 10^{Emissions}_{relative,i}/10\right) \quad [dBc]$$

### E.4.4 EVM equalizer spectrum flatness

For EVM equalizer spectrum flatness use EC(f) as defined in E.3.3. Note, EC(f) represents equalizer coefficient  $f \in F$ , f is the allocated subcarriers within the transmission bandwidth (( $|F|=12*L_{CRBs}$ )

From the acquired samples n functions EC(f) can be derived.

EC(f) is broken down to 2 functions:

$$\text{EC}_1(f), f \in Range \ 1$$

$$EC_2(f), f \in Range 2$$

Where Range 1 and Range 2 are as defined in Table 6.5.2.4.5-1 for normal condition and Table 6.5.2.4.5-2 for extreme condition

The following peak to peak ripple is calculated:

 $RP_1 = 20 * \log (max (|EC_1(f)|) / min(|EC_1(f)|))$ , which denote the maximum ripple in Range 1

 $RP_2 = 20 * log (max (| EC_2(f) |) / min(| EC_2(f) |))$ , which denote the maximum ripple in Range 2

 $RP_{12} = 20 * \log (max (|EC_1(f)|) / min(|EC_2(f)|))$ , which denote the maximum ripple between the upper side of Range 1 and lower side of Range 2

 $RP_{21} = 20 * \log (max (|EC_2(f)|) / min(|EC_1(f)|))$ , which denote the maximum ripple between the upper side of Range 2 and lower side of Range 1

### E.4.5 Frequency error and Carrier leakage

See E.3.1.

### E.4.6 EVM of Demodulation reference symbols (EVM<sub>DMRS</sub>)

For the purpose of EVM <sub>DMRS</sub>, the steps E.2.2 to E.4.2 are repeated 6 times, constituting 6 EVM <sub>DMRS</sub> sub-periods. The only purpose of the repetition is to cover the longer gross measurement period of EVM <sub>DMRS</sub> ( $6 \cdot n$  time slots) and to derive the FFT window timing per sub-period.

The bigger of the EVM results in one n TS period corresponding to the timing  $\Delta \tilde{c} - W/2$  or  $\Delta \tilde{c} + W/2$  is compared against the limit. (Clause E.4.2) This timing is re-used for EVM <sub>DMRS</sub> in the equivalent EVM <sub>DMRS</sub> sub-period.

For EVM the demodulation reference symbols are excluded, while the data symbols are used. For EVM<sub>DMRS</sub> the data symbols are excluded, while the demodulation references symbols are used. This is illustrated in figure E.4.6-1

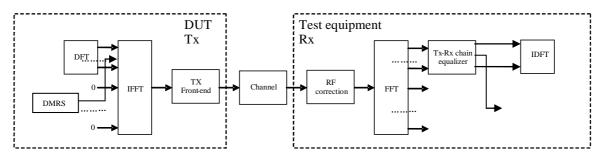


Figure E.4.6-1: EVM<sub>DMRS</sub> measurement points

Re-use the following formula from E.3.3:

$$Z'(f,t) = MS(f,t) \cdot EC(f)$$

To calculate  $EVM_{DMRS}$ , the data symbol (t=0,1,3,4,5,6,8,9,10,12,13) in Z'(f,t) are excluded and only the reference symbols (t=2,7,11) is used.

The EVM  $_{DMRS}$  is the difference between the ideal waveform and the measured and equalized waveform for the allocated RB(s)

$$EVM_{DMRS} = \sqrt{\frac{\sum_{t \in T} \sum_{f \in F} \left| Z^{-1}(f, t) - I(f, t) \right|^2}{\left| T \left| \cdot P_0 \cdot \left| F \right| \right|}},$$

where

t covers the count of demodulation reference symbols (i.e. symbols 2,7,11 in each slot, so count=3)

f covers the count of demodulation reference symbols within the allocated bandwidth. ( $|F|=12*L_{CRBs}$  (with  $L_{CRBs}$ : number of allocated resource blocks)).

Z'(f,t) are the samples of the signal evaluated for the EVM <sub>DMRS</sub>

I(f, t) is the ideal signal reconstructed by the measurement equipment, and

 $P_0$  is the average power of the ideal signal. For normalized modulation symbols  $P_0$  is equal to 1.

n such results are generated per measurement sub-period.

### E.4.6.1 1<sup>st</sup> average for EVM DMRS

EVM  $_{\text{DMRS}}$  is averaged over all basic EVM  $_{\text{DMRS}}$  measurements in one sub-period

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The averaging comprises n UL slots

$$1stEVM_{DMRS} = \sqrt{\frac{1}{n} \sum_{i=1}^{n} (EVM_{DMRS,i})^2}$$

The timing is taken from the EVM for the data. 6 of those results are achieved from the samples. In general the timing is not the same for each result.

#### E.4.6.2 Final average for EVM DMRS

$$finalEVM_{DMRS} = \sqrt{\frac{1}{6} \sum_{i=1}^{6} (1stEVM_{DMRS,i})^2}$$

## E.5 EVM and inband emissions for PUCCH

For the purpose of worst case testing, the PUCCH shall be located on the edges of the Transmission Bandwidth Configuration (6,15,25,50,75,100 RBs).

The EVM for PUCCH (EVM<sub>PUCCH</sub>) is averaged over n slots, where

$$n = \begin{cases} 30, \text{ for } 60 \text{ kHz SCS} \\ 60, \text{ for } 120 \text{ kHz SCS} \end{cases}.$$

At least *n* TSs shall be transmitted by the UE without power change. SRS multiplexing shall be avoided during this period. The following transition periods are applicable: One OFDM symbol on each side of the slot border (instant of band edge alternation).

The description below is generic in the sense that all 5 PUCCH formats are covered. Although the number of OFDM symbols in one slot can be different from 7 (depending on the format, configuration and cyclic prefix length), the text below uses 7 without excluding the others.

### E.5.1 Basic principle

The basic principle is the same as described in E.2.1

### E.5.2 Output signal of the TX under test

The output signal of the TX under test is processed same as described in E.2.2

### E.5.3 Reference signal

The reference signal is defined same as in E.2.3. Same as in E.2.3,  $i_1(v)$  is the ideal reference for EVM<sub>PUCCH</sub> and  $i_2(v)$  is used to estimate the FFT window timing.

Note PUSCH is off during the PUCCH measurement period.

### E.5.4 Measurement results

The measurement results are:

- EVM<sub>PUCCH</sub>
- Inband emissions with the sub-results: General in-band emission, IQ image (according to: 38.101. Annex F.4, Clause starting with: "At this stage the ....")

### E.5.5 Measurement points

The measurement points are illustrated in the Figure E.2.5-1.

### E.5.6 Pre FFT minimization process

The pre FFT minimisation process is the same as describes in clause E.3.1.

NOTE: although an exclusion period for EVM<sub>PUCCH</sub> is applicable in E.5.9.1, the pre FFT minimisation process is done over the complete slot.

RF error, and carrier leakage are necessary for best fit of the measured signal towards the ideal signal in the pre FFT domain. However they are not used to compare them against the limits.

### E.5.7 Timing of the FFT window

Timing of the FFT window is estimated with the same method as described in E.3.2.

### E.5.8 Post FFT equalisation

The post FFT equalisation is described separately without reference to E.3.3:

Perform 14 FFTs on z'(v), one for each OFDM symbol in a slot using the timing  $\Delta \tilde{c}$ , including the demodulation reference symbol. The result is an array of samples, 14 in the time axis t times 2048 in the frequency axis f. The samples represent the OFDM symbols (data and reference symbols) in the allocated RBs and inband emissions in the non allocated RBs within the transmission BW.

Only the allocated resource blocks in the frequency domain are used for equalisation.

The nominal reference symbols and **nominal** OFDM data symbols are used to equalize the measured data symbols.

Note: (The nomenclature inside this note is local and not valid outside)

The nominal OFDM data symbols are created by a demodulation process. A demodulation process as follows is recommended:

- 1. Equalize the measured OFDM data symbols using the reference symbols for equalisation. Result: Equalized OFDM data symbols
- 2. Decide for the nearest constellation point, however not independent for each subcarrier in the RB. 12 constellation points are decided dependent, using the applicable CAZAC sequence. Result: Nominal OFDM data symbols

At this stage we have an array of Measured data-Symbols and reference-Symbols (MS(f,t))

versus an array of Nominal data-Symbols and reference Symbols (NS(f,t))

The arrays comprise in sum 7 data and reference symbols, depending on the PUCCH format, in the time axis and the number of allocated sub-carriers in the frequency axis.

MS(f,t) and NS(f,t) are processed with a least square (LS) estimator, to derive one equalizer coefficient per time slot and per allocated subcarrier. EC(f)

$$EC(f) = \frac{\sum_{t=0}^{6} NS(f,t)^* NS(f,t)}{\sum_{t=0}^{6} MS(f,t)^* NS(f,t)}$$

With \* denoting complex conjugation.

EC(f) are used to equalize the OFDM data together with the demodulation reference symbols by:

 $Z'(f,t) = MS(f,t) \cdot EC(f)$ 

With · denoting multiplication.

Z'(f,t) is used to calculate EVM<sub>PUCCH</sub>, as described in E.5.9 1

NOTE: although an exclusion period for EVM<sub>PUCCH</sub> is applicable in E.5.9.1, the post FFT minimisation process is done over 7 OFDM symbols.

The samples of the non allocated resource blocks within the transmission bandwidth configuration in the post FFT domain are called Y(f,t) (f covering the non allocated subcarriers within the transmission bandwidth configuration, t covering the OFDM symbols during 1 slot).

### E.5.9 Derivation of the results

#### E.5.9.1 EVMPUCCH

For EVM<sub>PUCCH</sub> create two sets of Z'(f,t)., according to the timing " $\Delta \tilde{c}$  -W/2 and  $\Delta \tilde{c}$  +W/2" using the equalizer coefficients from E.5.8

The  $EVM_{PUCCH}$  is the difference between the ideal waveform and the measured and equalized waveform for the allocated RB(s)

$$EVM_{PUCCH} = \sqrt{\frac{\sum_{t \in T} \sum_{f \in F} \left| Z^{-1}(f, t) - I(f, t) \right|^2}{\left| T \left| \cdot P_0 \cdot \left| F \right| \right|}}$$

where

the OFDM symbols next to transition boarders (instant of PUCCH frequency hopping) are excluded:

t covers less than the count of demodulated symbols in the slot (|T|= 5)

f covers the count of subcarriers within the allocated bandwidth. (|F|=12)

Z'(f,t) are the samples of the signal evaluated for the EVM<sub>PUCCH</sub>

I(f, t) is the ideal signal reconstructed by the measurement equipment, and

 $P_0$  is the average power of the ideal signal. For normalized modulation symbols  $P_0$  is equal to 1.

From the acquired samples  $2n \text{ EVM}_{\text{PUCCH}}$  value can be derived, *n* values for the timing  $\Delta \tilde{c} - W/2$  and *n* values for the timing  $\Delta \tilde{c} + W/2$ 

### E.5.9.2 Averaged EVM<sub>PUCCH</sub>

EVM<sub>PUCCH</sub> is averaged over all basic EVM<sub>PUCCH</sub> measurements

The averaging comprises n UL slots

$$\overline{EVM}_{PUCCH} = \sqrt{\frac{1}{n} \sum_{i=1}^{n} (EVM_{PUCCH,i})^{2}}$$

The averaging is done separately for timing  $\Delta \tilde{c} - W/2$  and  $\Delta \tilde{c} + W/2$  leading to  $\overline{EVM}_{PUCCH, low}$  and  $\overline{EVM}_{PUCCH, high}$ 

 $EVM_{PUCCH, final} = \max(\overline{EVM}_{PUCCH, low}, \overline{EVM}_{PUCCH, high})$  is compared against the test requirements.

### E.5.9.3 In-band emissions measurement

The in-band emissions are a measure of the interference falling into the non-allocated resources blocks

Create one set of Y(t,f) per slot according to the timing " $\Delta \tilde{c}$  "

For the non-allocated RBs the in-band emissions are calculated as follows

$$Emissions_{absolute}(\Delta_{RB}) = \begin{cases} \frac{1}{|T_s|} \sum_{t \in T_s} \sum_{\substack{max(f_{min}, (c_t + 12 \cdot \Delta_{RB} + \Delta f)) \\ min(f_{max}, (c_h + 12 \cdot \Delta_{RB} + \Delta f)) \\ min(f_{max}, (c_h + 12 \cdot \Delta_{RB} + \Delta f)) \\ \frac{1}{|T_s|} \sum_{t \in T_s} \sum_{\substack{c_h + (12 \cdot \Delta_{RB} - 11) + \Delta f \\ c_h + (12 \cdot \Delta_{RB} - 11) + \Delta f}} |Y(t, f)|^2, \Delta_{RB} < 0 \end{cases}$$

where

the upper formula represents the inband emissions below the allocated frequency block and the lower one the inband emissions above the allocated frequency block.

 $T_s$  is a set of  $|T_s|$  OFDM symbols in the measurement period,

 $\Delta_{RB}$  is the starting frequency offset between the allocated RB and the measured non-allocated RB (e.g.  $\Delta_{RB} = 1$  for the first upper or  $\Delta_{RB} = -1$  for the first lower adjacent RB),

 $f_{\min}$  and  $f_{\max}$  are the lower and upper edge of the UL system BW,

 $c_1$  and  $c_h$  are the lower and upper edge of the allocated BW,

 $\Delta f$  is the SCS, and

Y(t, f) is the frequency domain signal evaluated for in-band emissions as defined in the subsection E.5.8

The relative in-band emissions are, given by

$$Emissions_{relative}(\Delta_{RB}) = 10 * \log_{10} \frac{Emissions_{absolute}(\Delta_{RB})}{\frac{1}{|T_s| \cdot L_{CRBs}} \sum_{t \in T_s} \sum_{c_1}^{c_1 + (12 \cdot L_{CRBs} - 1) * \Delta f} |MS(t, f)|^2} [dB]$$

where

 $L_{CRBs}$  is the number of allocated RBs,

and MS(t, f) is the frequency domain samples for the allocated bandwidth, as defined in the subsection E.5.8

Although an exclusion period for EVM is applicable in E.5.9.1, the inband emissions measurement interval is defined over one complete slot in the time domain.

From the acquired samples n functions for inband emissions can be derived.

The in-band emissions are averaged over the *n* samples (equivalent to 10 UL subframes) with the same PUCCH position to prevent averaging of allocated and non-allocated RBs due to PUCCH frequency hopping:

$$\overline{Emissions}_{absolute}(\Delta_{RB}) = \frac{1}{n} \sum_{i=1}^{n} Emissions_{absolute,i}(\Delta_{RB})$$

$$\overline{Emissions}_{relative}(\Delta_{RB}) = 10 * \log_{10} \left(\frac{1}{n} \sum_{i=1}^{n} 10^{Emissions}_{relative,i}(\Delta_{RB})/10\right) \quad [dB]$$

Since the PUCCH allocation is always on the upper or lower band-edge, the opposite of the allocated one represents the IQ image, and the remaining inner RBs represent the general inband emissions. They are compared against different limits.

### E.6 EVM for PRACH

The description below is generic in the sense that all PRACH formats are covered. The numbers, used in the text below are taken from PRACH format B4 without excluding the other formats. The sampling rate for the PUSCH, 122.88 Mbps in the time domain, is re-used for the PRACH. The carrier spacing of the PUSCH is up to 48 times higher than that of PRACH depending on the PRACH format and SCS. This results in an oversampling factor *ovf* of up to 48, when acquiring the time samples for the PRACH. The pre-FFT algorithms (clauses E.6.6 and E.6.7) use all time samples, although oversampled. For the FFT the time samples are decimated by the *ovf*, resulting in the same FFT size as for the other transmit modulation tests. Decimation requires a decision, which samples are used and which ones are rejected. The algorithm in E.6.6, Timing of the FFT window, can also be used to decide about the used samples.

### E.6.1 Basic principle

The basic principle is the same as described in E.2.1

### E.6.2 Output signal of the TX under test

The output signal of the TX under test is processed same as described in E.2.2

The measurement period is different since 2 PRACH preambles are recorded for long preamble formats as defined in Table 6.3.3.1-1 in [9] and 10 preambles are recorded for short preamble formats as defined in Table 6.3.3.1-2 in [9].

### E.6.3 Reference signal

The test description in 6.4.2.1.4.1 is based on non-contention based access:

- PRACH configuration index (responsible for Preamble format, System frame number and subframe number)
- Preamble ID
- Preamble power

signalled to the UE, defines the reference signal unambiguously, such that no demodulation process is necessary to gain the reference signal.

The reference signal i(v) is constructed by the measuring equipment according to the relevant TX specifications, using the following parameters: the applicable Zadoff Chu sequence, nominal carrier frequency, nominal amplitude and phase for each subcarrier, nominal timing, no carrier leakage. It is represented as a sequence of samples at a sampling rate of 122.88 Mbps in the time domain.

### E.6.4 Measurement results

The measurement result is:

- EVMPRACH

### E.6.5 Measurement points

The measurement points are illustrated in the figure below:

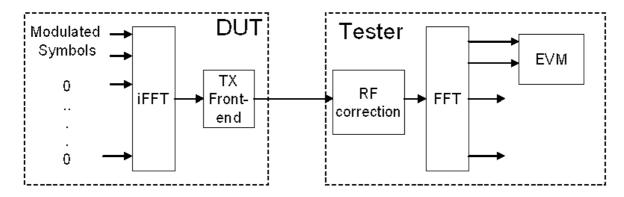


Figure E.6.5-1: Measurement points

### E.6.6 Pre FFT minimization process

The pre-FFT minimization process is applied to each PRACH preamble separately. The time period for the pre-FFT minimisation process includes the complete CP and Zadoff-Chu sequence (in other words, the power transition period is per definition outside of this time period) Sample timing, Carrier frequency and carrier leakage in z(v) are jointly varied in order to minimise the difference between z(v) and i(v). Best fit (minimum difference) is achieved when the RMS difference value between z(v) and i(v) is an absolute minimum.

After this process the samples z(v) are called  $z^0(v)$ .

RF error, and carrier leakage are necessary for best fit of the measured signal towards the ideal signal in the pre FFT domain. However they are not used to compare them against the limits.

### E.6.7 Timing of the FFT window

The FFT window length is  $8192 \cdot 2^{-\mu}$  samples for preamble format B4, however in the measurement period at least  $11936 \cdot 2^{-\mu}$  samples are taken where  $\mu \in \{2,3\}$ . The position in time for FFT must be determined.

In an ideal signal, the FFT may start at any instant within the cyclic prefix without causing an error. The TX filter, however, reduces the window. The EVM requirements shall be met within a window W<CP.

The reference instant for the FFT start is the centre of the reduced window, called  $\Delta \widetilde{c}$  ,

EVM is measured at the following two instants:  $\Delta \tilde{c} = W/2$  and  $\Delta \tilde{c} + W/2$ .

The timing of the measured signal  $z^{0}(v)$  with respect to the ideal signal i(v) is determined in the pre FFT domain as follows:

Correlation between  $z^0(v)$  and i(v) will result in a correlation peak. The meaning of the correlation peak is approx. the "impulse response" of the TX filter. The correlation peak, (the highest, or in case of more than one, the earliest) indicates the timing in the measured signal with respect to the ideal signal.

W is different for different preamble formats and shown in Table E.6.7-1 for  $L_{RA} = 139$  and  $\Delta f^{RA} = 15 \cdot 2^{\mu}$  kHz where  $\mu \in \{2,3\}$ .

Preamble format	$\begin{array}{c} \textbf{Cyclic} \\ \textbf{prefix} \\ \textbf{length} \ N_{cp} \end{array}$	Nominal FFT size <sup>1</sup>	EVM window length <i>W</i> in FFT samples	Ratio of <i>W</i> to CP*	
A1	1152·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	576·2 <sup>-µ</sup>	50.0%	
A2	2304·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	1728·2 <sup>-µ</sup>	75.0%	
A3	3456·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	2880·2 <sup>-µ</sup>	83.3%	
B1	864·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	288·2 <sup>-µ</sup>	33.3%	
B2	1440·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	864·2 <sup>-µ</sup>	60.0%	
B3	2016·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	1440·2 <sup>-µ</sup>	71.4%	
B4	3744·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	3168·2 <sup>-µ</sup>	84.6%	
C0	4960·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	4384·2 <sup>-µ</sup>	88.4%	
C2	8192·2 <sup>-µ</sup>	8192·2 <sup>-µ</sup>	7616·2 <sup>-µ</sup>	93.0%	
s	scaling of the window length is applied.				
Note 2: T	ote 2: These percentages are informative.				

Table E.6.7-1 EVM window length for PRACH formats for  $L_{\rm RA}$  =139

The number of samples, used for FFT is reduced compared to  $z^{0}(v)$ . This subset of samples is called z''(v).

The sample frequency 122.88 MHz is oversampled with respect to the PRACH-subcarrier spacing of  $\Delta f^{RA} = 15 \cdot 2^{\mu}$  kHz. EVM is based on 8192·2<sup>- $\mu$ </sup> samples per PRACH preamble and requires decimation of the time samples by the factor of  $12 \cdot 2^{\mu}$ . The final number of samples per PRACH preamble, used for FFT is reduced compared to z<sup>"</sup>(v) by the same factor. This subset of samples is called z'(v).

### E.6.8 Post FFT equalisation

Equalisation is not applicable for the PRACH.

### E.6.9 Derivation of the results

#### E.6.9.1 EVMPRACH

Perform FFT on z'(v) and i(v) using the FFT timing  $\Delta \tilde{c} - W/2$  and  $\Delta \tilde{c} + W/2$ .

For format B4 the first and the repeated preamble sequence are FFT-converted separately using the standard FFT length of 8192.

The  $EVM_{PRACH}$  is the difference between the ideal waveform and the measured and equalized waveform for the allocated RB(s).

$$EVM_{PRACH} = \sqrt{\frac{\sum_{t \in T} \sum_{f \in F} \left| Z^{-1}(f,t) - I(f,t) \right|^{2}}{\left| T \right| \cdot P_{0} \cdot \left| F \right|}}$$

where

t covers the count of demodulated symbols in the slot.

f covers the count of demodulated symbols within the allocated bandwidth.

Z'(f,t) are the samples of the signal evaluated for the EVM<sub>PRACH</sub>

I(f,t) is the ideal signal reconstructed by the measurement equipment, and

 $P_0$  is the average power of the ideal signal. For normalized modulation symbols  $P_0$  is equal to 1.

From the acquired samples  $2m \text{ EVM}_{\text{PRACH}}$  values can be derived, *m* values for the timing  $\Delta \tilde{c} -W/2$  and *m* values for the timing  $\Delta \tilde{c} +W/2$ .

### E.6.9.2 Averaged EVMPRACH

The PRACH EVM,  $EVM_{PRACH}$ , is averaged over *m* preamble sequence measurements.

$$\overline{EVM}_{\text{PRACH}} = \sqrt{\frac{1}{m} \sum_{i=1}^{m} \left( EVM_{\text{PRACH},i} \right)^2}$$

where m is the number of recorded preambles as defined in Annex E.6.2.

The averaging is done separately for timing  $\Delta \tilde{c} - W/2$  and  $\Delta \tilde{c} + W/2$  leading to  $\overline{EVM}_{PRACH,low}$  and  $\overline{EVM}_{PRACH,high}$ 

 $EVM_{PRACH, final} = \max(\overline{EVM}_{PRACH, low}, \overline{EVM}_{PRACH, high})$  is compared against the test requirements.

## Annex F (normative): Measurement uncertainties and Test Tolerances

## F.1 Acceptable uncertainty of Test System (normative)

The maximum acceptable uncertainty of the Test System is specified below for each test, where appropriate. The Test System shall enable the stimulus signals in the test case to be adjusted to within the specified range, and the equipment under test to be measured with an uncertainty not exceeding the specified values. Care should be taken to ensure that each conformance test implementation including the OTA chamber aspects meets the specified measurement uncertainty for each test case by requiring the test laboratory to maintain a detailed measurement uncertainty report showing compliance to all the measurement uncertainty requirements. The detailed measurement uncertainty report would contain the justification for each measurement uncertainty component and its value and distribution. The derivation of these values is based on the minimum conformance requirements plus relaxation, i.e., test tolerance is not to be considered. All ranges and uncertainties are absolute values, and are valid for a confidence level of 95 %, unless otherwise stated.

A confidence level of 95 % is the measurement uncertainty tolerance interval for a specific measurement that contains 95 % of the performance of a population of test equipment.

The downlink signal uncertainties apply at the defined quiet zone with the UE properly positioned in the quiet zone. The uplink signal uncertainties apply at the measurement equipment with the UE positioned properly in the quiet zone.

### F.1.1 Measurement of test environments

TBD

### F.1.2 Measurement of transmitter

Editor's note: The measurement uncertainties for 6.5.2.1 Spectrum Emission Mask and 6.5.2.3 Adjacent Channel Leakage Ratio are based on a preliminary MU assessment and require an approval of the uncertainty contributors to be included in the uncertainty assessment as well as the contributors need further technical analysis.

Sub clause	Maximum Test System Uncertainty	Derivation of MTSU
6.2.1.1 UE maximum output	PC3	MTSU = 1.00 x MU (from Table
power (EIRP)	Minimum peak EIRP, Max EIRP	B.3-2-2 in TR 38.903)
	Quiet Zone size ≤ 30 cm	
	±4.89 dB (FR2a)	
	±5.09 dB (FR2b)	
6.2.1.1 UE maximum output	PC3	MTSU = 1.00 x MU (from Table
power (TRP)	Max TRP	B.3-2-2 in TR 38.903)
,	Quiet Zone size ≤ 30 cm	,
	±4.42 dB (FR2a)	
	±4.62 dB (FR2b)	
6.2.1.2 UE maximum output	PC3	MTSU = 1.00 x MU (from Table
power (Spherical coverage)	Quiet Zone size ≤ 30 cm	B.3-2-4 in TR 38.903)
power (oprierieal coverage)	±4.60 dB (FR2a)	D.0 2 4 III 11( 00.000)
	±5.20 dB (FR2b)	
6.2.2 UE maximum output	PC3	MTSU = 1.00 x MU (from Table
power for modulation / channel	Quiet Zone size $\leq 30$ cm	B.4.4.2 in TR 38.903)
bandwidth		D.4.4.2 III TR 30.903)
Danuwiutn	±4.92 dB (FR2a)	
	±5.10 dB (FR2b)	
6.2.3 UE maximum output	TBD	
power with additional		
requirements		
6.2.4 Configured transmitted	TBD	
power		
6.2A.1.1.1 UE maximum output	Intra-band contiguous CA	
power - EIRP and TRP for CA	Maximum aggregated BW ≤ 400MHz	
(2UL CA)	Same as 6.2.1.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.2A.1.2.1 Spherical coverage	Intra-band contiguous CA	
for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.2.1.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	100	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6 24 1 2 2 Spherical approva	Intra-band contiguous CA	
6.2A.1.2.2 Spherical coverage for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
IOI CA (SUL CA)		
	Same as 6.2.1.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.2A.1.2.3 Spherical coverage	Intra-band contiguous CA	
for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.2.1.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.2A.1.2.4 Spherical coverage	Intra-band contiguous CA	
for CA (5UL CA)	TBD	
6.2A.1.2.5 Spherical coverage	Intra-band contiguous CA	
for CA (6UL CA)	TBD	
6.2A.1.2.6 Spherical coverage		
for CA (7UL CA)	Intra-band contiguous CA	
	TBD	1

 Table F.1.2-1: Maximum Test System Uncertainty (MTSU) for transmitter tests

6.2A.1.2.7 Spherical coverage for CA (8UL CA)	Intra-band contiguous CA TBD	
6.2A.1.1.2 UE maximum output	Intra-band contiguous CA	
power - EIRP and TRP for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.2A.2.1 UE maximum output power reduction for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2	MTSU = 1.00 x MU (from Table B.4.2-2 in TR 38.903)
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.3.1 Minimum output power	PC1 Minimum peak EIRP, Max EIRP Quiet Zone size ≤ 30 cm FFS (FR2a) FFS dB (FR2b)	
	<u>PC3</u> Minimum peak EIRP, Max EIRP Quiet Zone size ≤ 30 cm ±6.15 dB (FR2a & FR2b)	
6.3.2 Transmit OFF power	PC3: Quiet Zone size ≤ 30 cm ±5.49 dB (FR2a)	MTSU = 1.00 x MU (from Table B.8-2-2 in TR 38.903)
6.3.3.2 General ON/OFF time mask	PC3: ON power: TBD OFF power: Quiet Zone size ≤ 30 cm ±6.15 dB (FR2a & FR2b)	
6.3.3.4 PRACH time mask	PC3: PRACH power: TBD OFF power: Quiet Zone size ≤ 30 cm ±6.15 dB (FR2a & FR2b)	
6.3.3.6 SRS time mask	TBD	
6.3.4.2 Absolute power tolerance	<u>PC3</u> Quiet Zone size ≤ 30 cm ±TBD dB (FR2a) ±TBD dB (FR2b)	MTSU = 1.00 x MU (from Table TBD in TR 38.903)
6.3.4.3 Relative power tolerance	TBD	
6.3.4.4 Aggregate power tolerance	TBD	
6.3A.1.1 Minimum output power for CA (2UL CA)	TBD	
6.3A.1.2 Minimum output power for CA (3UL CA)	TBD	

m aggregated BW ≤ 400MHz	
m aggregated BW > 400MHz	
nd non-contiguous, Inter-band CA	
m aggregated BW ≤ 400MHz	
m aggregated BW > 400MHz	
nd non-contiguous, Inter-band CA	
m aggregated BW ≤ 400MHz	
m aggregated BW > 400MHz	
nd non-contiguous, Inter-band CA	
one size ≤ 30cm IB (FR2a)	OFF Power MTSU = 1.00 x MU (from Table Table B.8-2-4 in TR 38.903) ON Power TBD
one size ≤ 30cm R2a)	
one size ≤ 30cm IB (FR2a)	OFF Power MTSU = 1.00 x MU (from Table Table B.8-2-4 in TR 38.903) ON Power TBD
one size ≤ 30cm R2a) R2b)	
nd contiguous CA m aggregated BW ≤ 400MHz	
m aggregated BW > 400MHz	
nd non-contiguous, Inter-band CA	
	Ind contiguous CA Im aggregated BW < 400MHz is 6.3.2         Im aggregated BW > 400MHz         Ind non-contiguous, Inter-band CA Im aggregated BW < 400MHz is 6.3.2         Im aggregated BW > 400MHz         Ind contiguous CA Im aggregated BW > 400MHz         Im aggregated BW > 400MHz

6.3A.4.2.2 Absolute power	Intra-band contiguous CA	
tolerance for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.3 Absolute power	Intra-band contiguous CA	
tolerance for CA (4UL CA)	Maximum aggregated BW $\leq$ 400MHz Same as 6.3.4.2 for each CC.	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.4 Absolute power	Intra-band contiguous CA	1
tolerance for CA (5UL CA)	Maximum aggregated BW ≤ 400MHz	
- (	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.5 Absolute power	Intra-band contiguous CA	
tolerance for CA (6UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intro band non-contiguous Inter band CA	
	Intra-band non-contiguous, Inter-band CA TBD	
6.3A.4.2.6 Absolute power	Intra-band contiguous CA	
tolerance for CA (7UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.7 Absolute power	Intra-band contiguous CA	
tolerance for CA (8UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intro bond non contiguous, later band OA	
	Intra-band non-contiguous, Inter-band CA TBD	
6.4.1 Frequency error		MTSU = 1.00 x MU (from B.10.1
6.4.1 Frequency error	± 0.01 ppm	
6 4 2 1 Error vector magnitude	ТВО	and B.10.2 in TR 38.903)
6.4.2.1 Error vector magnitude	TBD	
6.4.2.2 Carrier leakage 6.4.2.3 In-band emissions	TBD	
6.4.2.4 EVM equalizer spectrum flatness	TBD	

6.4.2.5 EVM equalizer spectrum	TBD	
flatness for BPSK modulation		
6.4A.1.1 Frequency error for CA	Intra-band contiguous CA	
(2UL CA)	Maximum aggregated BW ≤ 400MHz	
(202 0/1)	Same as 6.4.1	
	Same as 0.4.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.4A.1.2 Frequency error for CA	Intra-band contiguous CA	
(3UL CA)	Maximum aggregated BW ≤ 400MHz	
(302 07)	Same as 6.4.1	
	Same as 0.4.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.4A.1.3 Frequency error for CA	Intra-band contiguous CA	
(4UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.4.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.4A.2.1.1 Error Vector	TBD	
magnitude for CA (2UL CA)		
6.4A.2.1.2 Error Vector	TBD	
magnitude for CA (3UL CA)		
6.4A.2.1.3 Error Vector	TBD	
magnitude for CA (4UL CA)		
6.4A.2.1.4 Error Vector	TBD	
magnitude for CA (5UL CA)	700	
6.4A.2.1.5 Error Vector	TBD	
magnitude for CA (6UL CA)		
6.4A.2.1.6 Error Vector	TBD	
magnitude for CA (7UL CA)		
6.4A.2.1.7 Error Vector	TBD	
magnitude for CA (8UL CA)		
6.4A.2.2.1 Carrier leakage for	TBD	
CA (2UL CA)		
6.4A.2.2.2 Carrier leakage for	TBD	
CA (3UL CA)		
6.4A.2.2.3 Carrier leakage for	TBD	
CA (4UL CA)		
6.4A.2.3.1 In-band emissions	TBD	
for CA (2UL CA)		
6.4A.2.3.2 In-band emissions	TBD	
for CA (3UL CA)		
6.4A.2.3.3 In-band emissions	TBD	
for CA (4UL CA)		
6.4A.2.3.4 In-band emissions	TBD	
for CA (5UL CA)		
6.4A.2.3.5 In-band emissions	TBD	
for CA (6UL CA)		
6.4A.2.3.6 In-band emissions	TBD	
for CA (7UL CA)		
6.4A.2.3.7 In-band emissions	TBD	
for CA (8UL CA)	<u></u>	
6.4A.2.2.4 Carrier leakage for	TBD	
CA (5UL CA)		
6.4A.2.2.5 Carrier leakage for	TBD	
CA (6UL CA)		
· · · · · ·	•	•

6.4A.2.2.6 Carrier leakage for CA (7UL CA)	TBD	
6.4A.2.2.7 Carrier leakage for CA (8UL CA)	TBD	
6.5.1 Occupied bandwidth	TBD	
6.5.2.1 Spectrum Emission Mask	Quiet Zone size $\leq$ 30 cm ±4.94 dB (FR2a) ±5.32 dB (FR2b)	MTSU = 1.00 x MU (from Table B.16.2-2, B.16.2-3 in TR 38.903)
6.5.2.3 Adjacent Channel Leakage Ratio	Quiet Zone size ≤ 30cm FR2a: ±5.63 dB (BW 50MHz) ±6.09 dB (BW 100MHz) ±6.09 dB (BW 200MHz) ±6.09 dB (BW 400MHz) FR2b: ±6.09 dB (BW 50MHz) ±6.09 dB (BW 50MHz) ±6.09 dB (BW 100MHz)	MTSU = 1.00 x MU (from Table Table B.17-1 in TR 38.903)
	±6.09 dB (BW 200MHz) ±6.09 dB (BW 400MHz)	
6.5.3.1 Transmitter Spurious emissions	Quiet Zone size $\leq$ 30 cm Maximum in-band BW $\leq$ 400MHz ±5.14 dB (6GHz $\leq$ f $\leq$ 12.75GHz) ±5.11 dB (12.75GHz $<$ f $\leq$ 23.45GHz) ±5.41 dB (23.45GHz $<$ f $<$ 40.8GHz)	MTSU = 1.00 x MU (from Table B.18-1 in TR 38.903)
	±7.42 dB (40.8GHz ≤ f ≤ 66GHz) ±[7.72] dB (66GHz ≤ f ≤ 80GHz)	
6.5.3.2 Spurious emission band UE co-existence	Quiet Zone size ≤ 30 cm Maximum in-band BW ≤ 400MHz Protected band n260, n261, n257: ±6.00 dB	MTSU = 1.00 x MU (from Table B.18-1a in TR 38.903)
	Protected frequency 57 GHz $\leq$ f $\leq$ 66GHz: ±8.01 dB Protected frequency 36 GHz $\leq$ f $\leq$ 37GHz: ±6.00 dB	
6.5.3.3 Additional Spurious emission	TBD	
6.5A.1.1 Occupied bandwidth for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.1.2 Occupied bandwidth for CA (3UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	

6.5A.1.3 Occupied bandwidth	Intra-band contiguous CA	
for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.1.4 Occupied bandwidth	TBD	
for CA (5UL CA)	100	
6.5A.1.5 Occupied bandwidth	TBD	
	עסו	
for CA (6UL CA)		
6.5A.1.6 Occupied bandwidth	TBD	
for CA (7UL CA)		
6.5A.1.7 Occupied bandwidth	TBD	
for CA (8UL CA)		
	Intro hand continuous CA	
6.5A.2.1.1 Spectrum Emission	Intra-band contiguous CA	
Mask for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.2.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	IBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.2.1.2 Spectrum Emission	Intra-band contiguous CA	
Mask for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.2.1	
	Game as 0.0.2.1	
	Maximum a new rated DW/ 400MU	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	ТВД	
6.5A.2.1.3 Spectrum Emission	Intra-band contiguous CA	
Mask for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz	
Mask IOI CA (40L CA)		
	Same as 6.5.2.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.2.1.4 Spectrum Emission	TBD	
Mask for CA (5UL CA)		
6.5A.2.1.5 Spectrum Emission	TBD	
Mask for CA (6UL CA)		
6.5A.2.1.6 Spectrum Emission	TBD	
Mask for CA (7UL CA)		
	TOD	
6.5A.2.1.7 Spectrum Emission	TBD	
Mask for CA (8UL CA)		
6.5A.2.2.1 Adjacent channel	Intra-band contiguous CA	MTSU = 1.00 x MU (from Table
leakage ratio for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	B.17.2-2 and Table B.17.2-4 in TR
	Same as 6.5.2.3	38.309)
	Meximum entreneted DM/ 400ML	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	

6.5A.2.2.2 Adjacent channel	Intra-band contiguous CA	
leakage ratio for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.2.3	
	Maximum angregated DM(+ 400ML	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.2.2.3 Adjacent channel	Intra-band contiguous CA	
leakage ratio for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz	
······g·····(·····,	Same as 6.5.2.3	
	Maximum aggregated BW > 400MHz	
	TBD	
	עפו	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.2.2.4 Adjacent channel	TBD	
leakage ratio for CA (5UL CA)		
6.5A.2.2.5 Adjacent channel	TBD	
leakage ratio for CA (6UL CA)		
6.5A.2.2.6 Adjacent channel	TBD	
leakage ratio for CA (7UL CA)		
6.5A.2.2.7 Adjacent channel	TBD	
leakage ratio for CA (8UL CA)		
6.5A.3.1.1 Transmitter Spurious	Intra-band contiguous CA	
emissions for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.3.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.3.1.2 Transmitter Spurious	Intra-band contiguous CA	
emissions for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
, , ,	Same as 6.5.3.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6 5A 2 1 2 Transmitter Sourieur		
6.5A.3.1.3 Transmitter Spurious	Intra-band contiguous CA	
emissions for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.3.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.3.1.4 Transmitter Spurious	TBD	
emissions for CA (5UL CA)		
6.5A.3.1.5 Transmitter Spurious	TBD	
emissions for CA (6UL CA)		
6.5A.3.1.6 Transmitter Spurious	TBD	
emissions for CA (7UL CA)		
6.5A.3.1.7 Transmitter Spurious	TBD	
emissions for CA (8UL CA)		
	1	

6.5A.3.2.1 Spurious emission	Intra-band contiguous CA	
band UE co-existence for CA	Maximum aggregated BW ≤ 400MHz	
(2UL CA)	Same as 6.5.3.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.3.2.2 Spurious emission	Intra-band contiguous CA	
band UE co-existence for CA	Maximum aggregated BW ≤ 400MHz	
(3UL CA)	Same as 6.5.3.2	
(362 8/)	Game as 0.0.0.2	
	Maximum a new rated DW/ 400MU	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.3.2.3 Spurious emission	Intra-band contiguous CA	
band UE co-existence for CA	Maximum aggregated BW ≤ 400MHz	
(4UL CA)	Same as 6.5.3.2	
	Jame as 0.0.0.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.3.2.4 Spurious emission	TBD	
band UE co-existence for CA		
(5UL CA)	700	
6.5A.3.2.5 Spurious emission	TBD	
band UE co-existence for CA		
(6UL CA)		
6.5A.3.2.6 Spurious emission	TBD	
band UE co-existence for CA		
(7UL CA)		
6.5A.3.2.7 Spurious emission	TBD	
band UE co-existence for CA		
(8UL CA)		
6.5A.3.3.1 Additional spurious	TBD	
emissions for CA (2UL CA)		
6.5A.3.3.2 Additional spurious	TBD	
emissions for CA (3UL CA)		
6.5A.3.3.3 Additional spurious	TBD	
emissions for CA (4UL CA)		
6.5A.3.3.4 Additional spurious	TBD	
emissions for CA (5UL CA)		
6.5A.3.3.5 Additional spurious	TBD	
emissions for CA (6UL CA)		
6.5A.3.3.6 Additional spurious	TBD	
emissions for CA (7UL CA)		
6.5A.3.3.7 Additional spurious	TBD	
emissions for CA (8UL CA)		
NOTE 1: FR2a: 23.45GHz ≤ f ≤ 3		
FR2b: 32.125GHz ≤ f		
FR2c: 40.8GHz ≤ f ≤ 4	14.3GHz	

# F.1.3 Measurement of receiver

Table F.1.3-1: Maximum Test System Uncertainty (MTSU) for receiver tests

Sub clause	Maximum Test System Uncertainty	Derivation of MTSU
7.3.2 Reference sensitivity	±5.19 dB (Quiet Zone size ≤ 30 cm, FR2a,	MTSU = 1.00 x MU (from Table
power level	FR2b)	B.19-2-2 in TR 38.903)
7.3.4 EIS spherical coverage	[±4.90] dB (Quiet Zone size ≤ 30 cm,	MTSU = 1.00 x MU (from Table
-	FR2a, FR2b)	B.19-2-2 in TR 38.903)
7.4 Maximum input level	TBD	
7.5 Adjacent channel selectivity	TBD	
7.6.2 In-band blocking	TBD	
7.9 Spurious emissions	Quiet Zone size ≤ 30 cm	MTSU = 1.00 x MU (from Table
	Maximum in-band BW ≤ 400MHz	B.18-1 in TR 38.903)
	For Band n257:	
	±5.50dB (6GHz ≤ f ≤ 12.75GHz)	
	±5.46dB (12.75GHz < f ≤ 23.45GHz)	
	±6.11dB (23.45GHz < f < 40.8GHz)	
	±7.65dB (40.8GHz ≤ f ≤ 66GHz)	
	±[7.95] dB (66GHz ≤ f ≤ 80GHz)	
NOTE 1: FR2a, FR2b and FR2c	are specified in Table F.1.2-1.	

# F.2 Interpretation of measurement results (normative)

The actual measurement uncertainty of the Test System for the measurement of each parameter shall be included in the test report.

The recorded value for the Test System uncertainty shall be, for each measurement, equal to or lower than the appropriate figure in clause F.1 of the present document.

If the Test System using one of the permitted test methods defined in TR38.903 [20] for a test is known to have a measurement uncertainty greater than that specified in clause F.1, it is still permitted to use this apparatus provided that an adjustment is made value as follows:

Any additional uncertainty in the Test System over and above that specified in clause F.1 shall be used to tighten the Test Requirement, making the test harder to pass. For some tests, for example receiver tests, this may require modification of stimulus signals. This procedure will ensure that a Test System not compliant with clause F.1 does not increase the chance of passing a device under test where that device would otherwise have failed the test if a Test System compliant with clause F.1 had been used.

# F.3 Test Tolerance and Derivation of Test Requirements (informative)

TBD

F.3.1 Measurement of test environments

TBD

#### F.3.2 Measurement of transmitter

Editor's note: This clause is incomplete. The following aspects are either missing or not yet determined:

- Influence of noise is subtracted from MTSU before calculating the TT for lower limit Tx test cases.

Sub clause	Test Tolerance (TT)	Formula for test requirement
6.2.1.1 UE maximum output	<u>PC3</u>	Minimum peak EIRP
power (EIRP)	Minimum peak EIRP IFF (Quiet Zone size ≤ 30 cm) 2.87 dB (FR2a) 2.87 dB (FR2b)	TT = 0.60 x (MTSU <sub>IFF</sub> - 0.1) (FR2a) TT = 0.60 x (MTSU <sub>IFF</sub> - 0.3) (FR2b)
	Max EIRP 0 dB	
6.2.1.1 UE maximum output power (TRP)	PC3 Max TRP IFF (Quiet Zone size ≤ 30 cm) 2.65 dB (FR2a) 2.77 dB (FR2b)	Max TRP TT = 0.60 x MTSUIFF
6.2.1.2 UE maximum output power (Spherical coverage)	PC1 TBD PC2 TBD	PC3 TT = 0.60 x (MTSU <sub>IFF</sub> - 0.3) (FR2a) TT = 0.60 x (MTSU <sub>IFF</sub> - 0.9) (FR2b)
	PC3 IFF (Quiet Zone size ≤ 30 cm) 2.58 dB (FR2a) 2.58 dB (FR2b)	
	PC4 TBD	
6.2.2 UE maximum output power for modulation / channel bandwidth	PC3 Minimum peak EIRP IFF (Quiet Zone size ≤ 30 cm) 3.11 dB (FR2a) 3.11 dB (FR2b)	Minimum peak EIRP TT = 0.65 x (MTSU <sub>IFF</sub> - 0.13) (FR2a) TT = 0.65 x (MTSU <sub>IFF</sub> - 0.31) (FR2b)
6.2.3 UE maximum output power with additional requirements	TBD	
6.2.4 Configured transmitted power	TBD	
6.2A.1.1.1 UE maximum output power - EIRP and TRP for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.2A.1.2.1 Spherical coverage for CA (2UL CA)	<u>Intra-band contiguous CA</u> Maximum aggregated BW ≤ 400MHz <u>Same as 6.2.1.2</u>	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.2A.1.2.2 Spherical coverage for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.2.1.2	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.2A.1.2.3 Spherical coverage for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz	

Same as 6.2.1.2	
Maximum aggregated BW > 400MHz TBD	
Intra-band non-contiguous, Inter-band CA TBD	

6.2A.1.2.4 Spherical coverage for CA (SUL CA)       Intra-band contiguous CA TBD         6.2A.1.2.5 Spherical coverage for CA (GUL CA)       Intra-band contiguous CA TBD         6.2A.1.2.6 Spherical coverage for CA (GUL CA)       Intra-band contiguous CA TBD         6.2A.1.2.7 Spherical coverage for CA (RUL CA)       Intra-band contiguous CA TBD         6.2A.1.2.10 Emaximum output power - EIRP and TRP for CA (3UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         1       Intra-band non-contiguous, Inter-band CA TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         1       Intra-band non-contiguous, Inter-band CA       Intra-band non-contiguous, Inter-band CA	
6.2A.1.2.5 Spherical coverage for CA (6UL CA)       Intra-band contiguous CA TBD         6.2A.1.2.6 Spherical coverage for CA (7UL CA)       Intra-band contiguous CA TBD         6.2A.1.2.7 Spherical coverage for CA (8UL CA)       Intra-band contiguous CA TBD         6.2A.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (3UL CA)       Intra-band contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         6.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         1       Intra-band non-contiguous, Inter-band CA Maximum aggregated BW ≤ 400MHz         TBD       Intra-band non-contiguous, Inter-band CA         1       Intra-band non-contiguous, Inter-band CA	
coverage for CA (6UL CA)TBD6.2A.1.2.6 SphericalIntra-band contiguous CAcoverage for CA (7UL CA)TBD6.2A.1.2.7 SphericalIntra-band contiguous CAcoverage for CA (8UL CA)TBD6.2A.1.1.2 UE maximumIntra-band contiguous CAoutput power - EIRP andIntra-band contiguous, Inter-band CATRP for CA (3UL CA)Maximum aggregated BW > 400MHzSame as 6.2.1.1Maximum aggregated BW > 400MHz6.2A.1.1.3 UE maximumIntra-band contiguous, Inter-band CAoutput power - EIRP andIntra-band contiguous, Inter-band CATRP for CA (4UL CA)Same as 6.2.1.16.2A.2.1 UE maximumIntra-band contiguous, Inter-band CATBDIntra-band non-contiguous, Inter-band CATBDIntra-band non-contiguous CAMaximum aggregated BW ≤ 400MHzCA)Same as 6.2.2Maximum aggregated BW ≤ 400MHzTBDIntra-band non-contiguous, Inter-band CATBDIntra-band non-contiguous, Inter-band CATBDIntra-band non-contiguous, Inter-band CAIBDIntra-band non-contiguous, Inter-band CAIBDIntra-band n	
6.2A.1.2.6 Spherical coverage for CA (7UL CA)       Intra-band contiguous CA TBD         6.2A.1.2.7 Spherical coverage for CA (8UL CA)       Intra-band contiguous CA TBD         6.2A.1.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz         6.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz TBD         1.1.1.3 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz TBD	
coverage for CA (7UL CA)TBD6.2A.1.2.7 Spherical coverage for CA (8UL CA)Intra-band contiguous CA6.2A.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)Intra-band contiguous CAMaximum aggregated BW $\leq$ 400MHzSame as 6.2.1.1Maximum aggregated BW > 400MHzTBDIntra-band non-contiguous, Inter-band CATBD6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band contiguous CA TBD6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band contiguous CA TBD6.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band non-contiguous, Inter-band CA TBD6.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band non-contiguous, Inter-band CA TBD6.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band non-contiguous, Inter-band CA TBDIntra-band non-contiguous, Inter-band CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.2Maximum aggregated BW $\leq$ 400MHz TBDIntra-band non-contiguous, Inter-band CA TBDIntra-band non-contiguous, Inter-band CA TBDIntra-band non-contiguous, Inter-band CA TBDIntra-band non-contiguous, Inter-band CA ITBDIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CA ITBDIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CA	
6.2A.1.2.7 Spherical coverage for CA (8UL CA)       Intra-band contiguous CA TBD         6.2A.1.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)       Intra-band contiguous CA Maximum aggregated BW $\leq 400$ MHz Same as 6.2.1.1         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW $\leq 400$ MHz Same as 6.2.1.1         6.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW $\leq 400$ MHz TBD         1.117-band contiguous CA TBD       Intra-band non-contiguous, Inter-band CA TBD         1.127-Band contiguous CA TBD       Maximum aggregated BW $\leq 400$ MHz TBD         1.127-Band contiguous CA TBD       Maximum aggregated BW $\leq 400$ MHz TBD         1.127-Band non-contiguous, Inter-band CA TBD       Maximum aggregated BW $\leq 400$ MHz TBD         1.127-Band non-contiguous, Inter-band CA       Maximum aggregated BW $\leq 400$ MHz TBD         1.127-Band non-contiguous, Inter-band CA       Maximum aggregated BW $\leq 400$ MHz	
coverage for CA (8UL CA)TBD6.2A.1.1.2 UE maximum output power - EIRP and TRP for CA (3UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.1.1Maximum aggregated BW > 400MHz TBDIntra-band non-contiguous, Inter-band CA TBD6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.1.16.2A.2.1 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.1.16.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz TBD6.2A.2.1 UE maximum output power as 6.2.2.1Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz TBD6.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz TBD1Intra-band contiguous, Inter-band CA TBD1Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.21Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz TBD2Intra-band non-contiguous, Inter-band CA TBD1Intra-band non-contiguous, Inter-band CA TBD1Intra-band non-contiguous, Inter-band CA TBD1Intra-band non-contiguous, Inter-band CA2Intra-band non-contiguous, Inter-band CA TBD3Intra-band non-contiguous, Inter-band CA4Intra-band non-contiguous, Inter-band CA4Intra-band non-contiguous, Inter-band CA <td></td>	
6.2A.1.1.2 UE maximum       Intra-band contiguous CA         output power - EIRP and       Maximum aggregated BW ≤ 400MHz         Same as 6.2.1.1       Maximum aggregated BW > 400MHz         B       Intra-band non-contiguous, Inter-band CA         TBD       Intra-band contiguous CA         6.2A.1.1.3 UE maximum       Intra-band contiguous, Inter-band CA         TBD       Intra-band contiguous CA         Maximum aggregated BW ≤ 400MHz       Same as 6.2.1.1         6.2A.1.1.3 UE maximum       Intra-band contiguous CA         output power - EIRP and       Maximum aggregated BW ≤ 400MHz         TRP for CA (4UL CA)       Same as 6.2.1.1         Maximum aggregated BW > 400MHz       Same as 6.2.1.1         Maximum aggregated BW > 400MHz       Same as 6.2.1.1         Maximum aggregated BW > 400MHz       TBD         Intra-band non-contiguous, Inter-band CA       TBD         Intra-band contiguous CA       Maximum aggregated BW > 400MHz         CA)       Maximum aggregated BW ≤ 400MHz         Same as 6.2.2       Maximum aggregated BW > 400MHz         Same as 6.2.2       Maximum aggregated BW > 400MHz         ID       Intra-band non-contiguous, Inter-band CA         TBD       Intra-band non-contiguous, Inter-band CA         ID       Intra-band non-contiguous, In	
output power - EIRP and TRP for CA (3UL CA)Maximum aggregated BW $\leq$ 400MHz Same as 6.2.1.1Maximum aggregated BW > 400MHz TBDIntra-band non-contiguous, Inter-band CA TBD6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.2.1.16.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD6.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD1.1.13 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD1.1.13 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD1.1.14 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD1.1.17 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous, Inter-band CA TBD1.1.17 UE maximum aggregated BW $\leq$ 400MHz Same as 6.2.2Intra-band non-contiguous, Inter-band CA TBD1.1.17 UE maximum aggregated BW $\leq$ 400MHz Same as 6.2.2Intra-band non-contiguous, Inter-band CA TBD	
TRP for CA (3UL CA)Same as $6.2.1.1^{\circ}$ Maximum aggregated BW > 400MHzTBDIntra-band non-contiguous, Inter-band CATBD6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)Maximum aggregated BW $\leq 400$ MHzSame as $6.2.1.1$ Maximum aggregated BW > 400MHzSame as $6.2.1.1$ Maximum aggregated BW > 400MHzTBDIntra-band non-contiguous, Inter-band CATBDIntra-band non-contiguous, Inter-band CATBDIntra-band non-contiguous, Inter-band CATBDIntra-band contiguous CApower reduction for CA (2UL CA)Maximum aggregated BW $\leq 400$ MHzSame as $6.2.2$ Maximum aggregated BW $\leq 400$ MHzSame as $6.2.2$ Maximum aggregated BW $\geq 400$ MHzTBDIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CAIntra-band non-contiguous, Inter-band CA	
Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≤ 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         Intra-band non-contiguous, Inter-band CA TBD       Intra-band non-contiguous, Inter-band CA	
TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW > 400MHz TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD	
Intra-band non-contiguous, Inter-band CA TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≤ 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≥ 400MHz TBD       Intra-band non-contiguous, Inter-band CA	
TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≤ 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         Intra-band non-contiguous, Inter-band CA       Intra-band non-contiguous, Inter-band CA	
TBD         6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≤ 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         Intra-band non-contiguous, Inter-band CA       Intra-band non-contiguous, Inter-band CA	
6.2A.1.1.3 UE maximum output power - EIRP and TRP for CA (4UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW ≤ 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         Intra-band non-contiguous, Inter-band CA       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz TBD         Intra-band non-contiguous, Inter-band CA       Intra-band non-contiguous, Inter-band CA	
output power - EIRP and TRP for CA (4UL CA)       Maximum aggregated BW ≤ 400MHz Same as 6.2.1.1         Maximum aggregated BW > 400MHz TBD       Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD       Intra-band contiguous CA Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA       Intra-band non-contiguous, Inter-band CA	
TRP for CA (4UL CA)Same as $6.2.1.1^{\circ}$ Maximum aggregated BW > 400MHz TBDIntra-band non-contiguous, Inter-band CA TBD6.2A.2.1 UE maximum output power reduction for CA (2UL CA)Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as $6.2.2$ Maximum aggregated BW $\leq$ 400MHz TBDIntra-band non-contiguous, Inter-band CA Maximum aggregated BW $\leq$ 400MHz Same as $6.2.2$ Intra-band non-contiguous, Inter-band CA TBDIntra-band non-contiguous, Inter-band CA	
Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA	
TBD         Intra-band non-contiguous, Inter-band CA         TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)         Intra-band contiguous CA         Maximum aggregated BW ≤ 400MHz         Same as 6.2.2         Maximum aggregated BW > 400MHz         TBD         Intra-band non-contiguous, Inter-band CA	
TBD         Intra-band non-contiguous, Inter-band CA         TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)         Intra-band contiguous CA         Maximum aggregated BW ≤ 400MHz         Same as 6.2.2         Maximum aggregated BW > 400MHz         TBD         Intra-band non-contiguous, Inter-band CA	
Intra-band non-contiguous, Inter-band CA TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA	
TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA	
TBD         6.2A.2.1 UE maximum output power reduction for CA (2UL CA)       Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.2.2         Maximum aggregated BW > 400MHz TBD         Intra-band non-contiguous, Inter-band CA	
power reduction for CA (2UL       Maximum aggregated BW ≤ 400MHz         CA)       Same as 6.2.2         Maximum aggregated BW > 400MHz         TBD         Intra-band non-contiguous, Inter-band CA	
CA)     Same as 6.2.2       Maximum aggregated BW > 400MHz       TBD       Intra-band non-contiguous, Inter-band CA	
Maximum aggregated BW > 400MHz TBD Intra-band non-contiguous, Inter-band CA	
TBD Intra-band non-contiguous, Inter-band CA	
TBD Intra-band non-contiguous, Inter-band CA	
Intra-band non-contiguous, Inter-band CA	
TBD	
6.3.1 Minimum output power PC3 Minimum EIRP	
$\frac{100}{\text{Minimum EIRP}} \qquad \qquad \text{TT} = 0.65 \text{ x} (\text{MTSU}_{\text{IFF}} - 1.0) (\text{FR})$	2a)
IFF (Quiet Zone size $\leq 30$ cm) TT = 0.65 x (MTSU <sub>IFF</sub> - 1.0) (FR2	
3.35 dB (FR2a)	
3.35 dB (FR2b)	
6.3.2 Transmit OFF power 0 dB	
6.3.3.2 General ON/OFF time PC3: ON Power	
mask <u>OFF Power</u> TBD Quiet Zone size ≤ 30cm	
0 dB	
0.00	
ON Power	
Quiet Zone size ≤ 30cm	
TBD (FR2a)	
TBD (FR2b)TBD	
6.3.3.4 PRACH time mask PC3: <u>ON Power</u>	
OFF Power TBD	
Quiet Zone size ≤ 30cm	
0 dB	
ON Power	
<u>ON Power</u> Quiet Zone size ≤ 30cm	
TBD (FR2a)	
TBD (FR2b)TBD	
6.3.4.2 Absolute power <u>PC3</u> PC3	
tolerance IFF (Quiet Zone size $\leq$ 30 cm) TT = TBD (FR2a)	
TBD dB (FR2a) TT = TBD (FR2b)	
TBD dB (FR2b)	
6.3.4.3 Relative power TBD	
tolerance	
6.3.4.4 Aggregate power TBD	
tolerance	

		1
6.3A.1.1 Minimum output	TBD	
power for CA (2UL CA) 6.3A.1.2 Minimum output	TBD	
power for CA (3UL CA)		
6.3A.1.3 Minimum output	TBD	
power for CA (4UL CA)		
6.3A.1.4 Minimum output	TBD	
power for CA (5UL CA)		
6.3A.1.5 Minimum output	TBD	
power for CA (6UL CA) 6.3A.1.6 Minimum output	TBD	
power for CA (7UL CA)		
6.3A.1.7 Minimum output	TBD	
power for CA (8UL CA)		
6.3A.2.1 Transmit OFF power	Intra-band contiguous CA	
for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.2	
	Maximum a serie sate d DM/ (0004115	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.2.2 Transmit OFF power	Intra-band contiguous CA	
for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.2.3 Transmit OFF power	Intra-band contiguous CA	
for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.3.2	
	Same as 6.3.2	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	011.0
6.3D.3.1 General ON/OFF time mask for UL MIMO	PC3:	ON Power TBD
	<u>OFF Power</u> Quiet Zone size ≤ 30cm	IBD
	0 dB	
	ON Power	
	Quiet Zone size ≤ 30cm	
	TBD (FR2a)	
6.3D.3.4 SRS time mask for	TBD (FR2b) PC3:	ON Power
UL MIMO	OFF Power	TBD
	Quiet Zone size ≤ 30cm	
	0 dB	
	ON Power	
	Quiet Zone size ≤ 30cm TBD (FR2a)	
	TBD (FR2b)	
6.3A.4.2.1 Absolute power	Intra-band contiguous CA	
tolerance for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.2 Absolute power	Intra-band contiguous CA	

tolerance for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	later band can continue to later band CA	
	Intra-band non-contiguous, Inter-band CA	
6 24 4 2 2 Absolute power		
6.3A.4.2.3 Absolute power tolerance for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz	
IDIETATICE TOT CA (40L CA)	Same as $6.3.4.2$ for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.4 Absolute power	Intra-band contiguous CA	
tolerance for CA (5UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
6.3A.4.2.5 Absolute power	IBD Intra-band contiguous CA	
tolerance for CA (6UL CA)	<u>Intra-band contiguous CA</u> Maximum aggregated BW ≤ 400MHz	
	Same as $6.3.4.2$ for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.6 Absolute power	Intra-band contiguous CA	
tolerance for CA (7UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.3A.4.2.7 Absolute power	Intra-band contiguous CA	
tolerance for CA (8UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.3.4.2 for each CC.	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.4.1 Frequency error	0.005 ppm	TT = 0.5 x MTSU
6.4.2.1 Error vector	0%, up to 64QAM	Minimum requirement + TT
magnitude		
6.4.2.2 Carrier leakage	TBD	
6.4.2.3 In-band emissions	TBD	
6.4.2.4 EVM equalizer	TBD	
spectrum flatness		
6.4.2.5 EVM equalizer	TBD	
spectrum flatness for BPSK		
modulation 6.4A.1.1 Frequency error for	Intra-band contiguous CA	
6.4A.1.1 Frequency error for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz	
	Same as $6.4.1$	
	Maximum aggregated BW > 400MHz	
	TBD	
1		
	Intra-band non-contiguous, Inter-band CA	
	Intra-band non-contiguous, Inter-band CA TBD	
6.4A.1.2 Frequency error for CA (3UL CA)		

	Same as 6.4.1	
	Same as 0.4.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA	
6.4A.1.3 Frequency error for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.4.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.4A.2.1.1 Error Vector	TBD	
magnitude for CA (2UL CA) 6.4A.2.1.2 Error Vector	TBD	
magnitude for CA (3UL CA)		
6.4A.2.1.3 Error Vector magnitude for CA (4UL CA)	TBD	
6.4A.2.1.4 Error Vector	TBD	
magnitude for CA (5UL CA) 6.4A.2.1.5 Error Vector	TBD	
magnitude for CA (6UL CA)		
6.4A.2.1.6 Error Vector magnitude for CA (7UL CA)	TBD	
6.4A.2.1.7 Error Vector	TBD	
magnitude for CA (8UL CA) 6.4A.2.2.1 Carrier leakage for	TBD	
CA (2UL CA)		
6.4A.2.2.2 Carrier leakage for CA (3UL CA)	TBD	
6.4A.2.2.3 Carrier leakage for	TBD	
CA (4UL CA) 6.4A.2.3.1 In-band emissions	TBD	
for CA (2UL CA) 6.4A.2.3.2 In-band emissions		
for CA (3UL CA)	TBD	
6.4A.2.3.3 In-band emissions for CA (4UL CA)	TBD	
6.4A.2.3.4 In-band emissions for CA (5UL CA)	TBD	
6.4A.2.3.5 In-band emissions for CA (6UL CA)	TBD	
6.4A.2.3.6 In-band emissions for CA (7UL CA)	TBD	
6.4A.2.3.7 In-band emissions for CA (8UL CA)	TBD	
6.4A.2.2.4 Carrier leakage for CA (5UL CA)	TBD	
6.4A.2.2.5 Carrier leakage for CA (6UL CA)	TBD	
6.4A.2.2.6 Carrier leakage for CA (7UL CA)	TBD	
6.4A.2.2.7 Carrier leakage for CA (8UL CA)	TBD	
6.5.1 Occupied bandwidth	0 kHz	Minimum requirement + TT
6.5.2.1 Spectrum Emission Mask	IFF (Quiet Zone size ≤ 30 cm) 3.21 dB (FR2a) 3.46 dB (FR2b)	TT = 0.65 x MTSU <sub>IFF</sub>
6.5.2.3 Adjacent Channel	Absolute requirement	TT = 0.65 x MTSU <sub>IFF</sub> + TT due to
Leakage Ratio	0 dB	metric change
	Relative requirement	TT due to metric change : 1.0 dB
	1	1

	IFF (Quiet Zone size ≤ 30 cm)	
	FR2a:	
	±4.66 dB (BW 50MHz)	
	±4.96 dB (BW 100MHz)	
	±4.96 dB (BW 200MHz)	
	±4.96 dB (BW 400MHz)	
	FDat	
	FR2b:	
	±4.96 dB (BW 50MHz)	
	±4.96 dB (BW 100MHz)	
	±4.96 dB (BW 200MHz)	
	±4.96 dB (BW 400MHz)	
6.5.3.1 Transmitter Spurious	0 dB	Minimum requirement + TT
emissions	0 dB	Minimum requirement LT
6.5.3.2 Spurious emission band UE co-existence	U UB	Minimum requirement + TT
	Intro hand contiguous CA	
6.5A.1.1 Occupied bandwidth	Intra-band contiguous CA	
for CA (2UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.5.1	
	Same as 6.5.1	
	Maximum answered DW/ 400MU	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intro bond non contiguous, later band OA	
	Intra-band non-contiguous, Inter-band CA	
6.54.1.2 Occupied bendwidth	TBD	
6.5A.1.2 Occupied bandwidth	Intra-band contiguous CA	
for CA (3UL CA)	Maximum aggregated BW ≤ 400MHz	
	Same as 6.5.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	lates have descention and based OA	
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.1.3 Occupied bandwidth	Intra-band contiguous CA	
for CA (4UL CA)	Maximum aggregated BW ≤ 400MHz Same as 6.5.1	
	Same as 0.5.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.1.4 Occupied bandwidth	ТВО	
for CA (5UL CA)		
6.5A.1.5 Occupied bandwidth	TBD	
for CA (6UL CA)		
6.5A.1.6 Occupied bandwidth	TBD	
for CA (7UL CA)	·	
6.5A.1.7 Occupied bandwidth	TBD	1
for CA (8UL CA)		
6.5A.2.1.1 Spectrum	Intra-band contiguous CA	
Emission Mask for CA (2UL	Maximum aggregated BW ≤ 400MHz	
CA)	Same as 6.5.2.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	
	TBD	
6.5A.2.1.2 Spectrum	Intra-band contiguous CA	
Emission Mask for CA (3UL	Maximum aggregated BW ≤ 400MHz	
CA)	Same as 6.5.2.1	
	Maximum aggregated BW > 400MHz	
	TBD	
	Intra-band non-contiguous, Inter-band CA	

	TBD	
6.5A.2.1.3 Spectrum Emission Mask for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.2.1	
	Maximum aggregated BW > 400MHz TBD	
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.2.1.4 Spectrum Emission Mask for CA (5UL CA)	TBD	
6.5A.2.1.5 Spectrum Emission Mask for CA (6UL CA)	TBD	
6.5A.2.1.6 Spectrum Emission Mask for CA (7UL CA)	TBD	
6.5A.2.1.7 Spectrum Emission Mask for CA (8UL CA)	TBD	
6.5A.2.2.1 Adjacent channel leakage ratio for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.2.3	TT = 0.65 x MTSU <sub>IFF</sub> + TT due to metric change
	Maximum aggregated BW > 400MHz TBD	TT due to metric change : 1.0 dB
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.2.2.2 Adjacent channel leakage ratio for CA (3UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.2.3	TT = 0.65 x MTSU <sub>IFF</sub> + TT due to metric change
	Maximum aggregated BW > 400MHz TBD	TT due to metric change : 1.0 dB
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.2.2.3 Adjacent channel leakage ratio for CA (4UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.2.3	TT = 0.65 x MTSU <sub>IFF</sub> + TT due to metric change
	Maximum aggregated BW > 400MHz TBD	TT due to metric change : 1.0 dB
	Intra-band non-contiguous, Inter-band CA TBD	
6.5A.2.2.4 Adjacent channel leakage ratio for CA (5UL CA)	TBD	
6.5A.2.2.5 Adjacent channel leakage ratio for CA (6UL CA)	TBD	
6.5A.2.2.6 Adjacent channel leakage ratio for CA (7UL CA)	TBD	
6.5A.2.2.7 Adjacent channel leakage ratio for CA (8UL CA)	TBD	
6.5A.3.1.1 Transmitter Spurious emissions for CA (2UL CA)	Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.3.1	
	Maximum aggregated BW > 400MHz TBD	

Intra-band non-contiguous, Inter-band CA TBD				
Intra-band contiguous CA Maximum aggregated BW $\leq$ 400MHz Same as 6.5.3.1				
Maximum aggregated BW > 400MHz TBD				
Intra-band non-contiguous, Inter-band CA TBD				
Intra-band contiguous CA Maximum aggregated BW ≤ 400MHz Same as 6.5.3.1				
Maximum aggregated BW > 400MHz TBD				
Intra-band non-contiguous, Inter-band CA TBD				
NOTE 1: $FR2a: 23.45GHz \le f \le 32.125GHz$ $FR2b: 32.125GHz \le f \le 40.8GHz$ $FR2c: 40.8GHz \le f \le 44.3GHz$				
	Intra-band contiguous CA         Maximum aggregated BW $\leq$ 400MHz         Same as 6.5.3.1         Maximum aggregated BW > 400MHz         TBD         Intra-band non-contiguous, Inter-band CA         TBD         Intra-band contiguous CA         Maximum aggregated BW $\leq$ 400MHz         Same as 6.5.3.1         Maximum aggregated BW $\leq$ 400MHz         Same as 6.5.3.1         Maximum aggregated BW $\geq$ 400MHz         Same as 6.5.3.1         Maximum aggregated BW $\geq$ 400MHz         TBD $\leq$ 32.125GHz $\leq$ 40.8GHz			

# F.3.3 Measurement of receiver

Sub clause	Test Tolerance (TT)	Formula for test requirement		
7.3.2 Reference sensitivity power level	IFF (Quiet Zone size ≤ 30 cm, FR2a, FR2b) 2.34 dB	TT = 0.45 x MTSUIFF		
7.3.4 EIS spherical coverage	IFF (Quiet Zone size ≤ 30 cm, FR2a, FR2b) 2.21 dB	PC3 TT = 0.45 x MTSUIFF		
7.4 Maximum input level	TBD			
7.5 Adjacent channel selectivity	<u>0 dB</u>	Wanted signal power + TT		
		T-put limit unchanged		
7.6.2 In-band blocking	<u>0 dB</u>	Wanted signal power + TT		
		T-put limit unchanged		
7.9 Spurious emissions	<u>0 dB</u>	Minimum requirement + TT		
		T-put limit unchanged		
NOTE 1: FR2a, FR2b and FR2c are specified in Table F.3.2-1.				

## Annex G (normative): Uplink Physical Channels

## G.0 Uplink Signal Levels

Please refer to Annex G.0 in TS 38.521-1 [13].

## G.1 General

Please refer to Annex G.1 in TS 38.521-1 [13].

# G.2 Set-up

Please refer to Annex G.2 in TS 38.521-1 [13].

## G.3 Connection

Please refer to Annex G.3 in TS 38.521-1 [13].

#### G.3.0 Measurement of Transmitter Characteristics

Please refer to Annex G.3.0 in TS 38.521-1 [13].

#### G.3.1 Measurement of Receiver Characteristics

Please refer to Annex G.3.1 in TS 38.521-1 [13].

## Annex H (normative): Statistical Testing

Editor's Note: Further investigate the technical details behind this statistical method to ensure that this is applicable for FR2 radiated test cases.

## H.1 General

This annex specifies mapping throughput to error ratio, pass fail limits and pass fail decision rules that are needed for measuring average throughput for a duration sufficient to achieve statistical significance for testing receiver characteristics.

## H.2 Statistical testing of receiver characteristics

#### H.2.1 General

The test of receiver characteristics is twofold.

- 1. A signal or a combination of signals is offered to the RX port(s) of the receiver.
- 2. The ability of the receiver to demodulate /decode this signal is verified by measuring the throughput.

In (2) is the statistical aspect of the test and is treated here.

The minimum requirement for all receiver tests is >95% of the maximum throughput.

All receiver tests are performed in static propagation conditions. No fading conditions are applied.

#### H.2.2 Mapping throughput to error ratio

- a) The measured information bit throughput R is defined as the sum (in kilobits) of the information bit payloads successfully received during the test interval, divided by the duration of the test interval (in seconds).
- b) In measurement practice the UE indicates successfully received information bit payload by signalling an ACK to the SS.

If payload is received, but damaged and cannot be decoded, the UE signals a NACK.

- c) Only the ACK and NACK signals, not the data bits received, are accessible to the SS. The number of bits is known in the SS from knowledge of what payload was sent.
- d) For the reference measurement channel, applied for testing, the number of bits is different in different subframes, however in a radio frame it is fixed during one test.
- e) The time in the measurement interval is composed of successfully received subframes (ACK), unsuccessfully received subframes (NACK) and no reception at all (DTX-subframes).
- f) DTX-subframes may occur regularly according the applicable reference measurement channel (regDTX). In real live networks this is the time when other UEs are served. In TDD these are the UL and special subframes. regDTX vary from test to test but are fixed within the test.
- g) Additional DTX-subframes occur statistically when the UE is not responding ACK or NACK where it should. (statDTX)

This may happen when the UE was not expecting data or decided that the data were not intended for it.

The pass / fail decision is done by observing the:

- number of NACKs
- number of ACKs and
- number of statDTXs (regDTX is implicitly known to the SS)

The ratio (NACK + statDTX) / (NACK + statDTX + ACK) is the Error Ratio (ER). Taking into account the time consumed by the ACK, NACK, and DTX-TTIs (regular and statistical), ER can be mapped unambiguously to throughput for any single reference measurement channel test.

#### H.2.3 Design of the test

The test is defined by the following design principles (see clause H.x, Theory....):

- 1. The early decision concept is applied.
- 2. A second limit is introduced: Bad DUT factor M>1
- 3. To decide the test pass:

Supplier risk is applied based on the Bad DUT quality

To decide the test fail

Customer Risk is applied based on the specified DUT quality

The test is defined by the following parameters:

- 1. Limit ER = 0.05 (Throughput limit = 95%)
- 2. Bad DUT factor M=1.5 (selectivity)
- 3. Confidence level CL = 95% (for specified DUT and Bad DUT-quality)

## H.2.4 Numerical definition of the pass fail limits

ne	ns <sub>p</sub>	ns <sub>f</sub>	ne	nsp	ns <sub>f</sub>	ne	ns <sub>p</sub>	ns <sub>f</sub>	ne	nsp	ns <sub>f</sub>
0	67	NA	39	763	500	78	1366	1148	117	1951	1828
1	95	NA	40	778	516	79	1381	1166	118	1965	1845
2	119	NA	41	794	532	80	1396	1183	119	1980	1863
3	141	NA	42	810	548	81	1412	1200	120	1995	1881
4	162	NA	43	826	564	82	1427	1217	121	2010	1899
5	183	NA	44	842	580	83	1442	1234	122	2025	1916
6	202	NA	45	858	596	84	1457	1252	123	2039	1934
7	222	NA	46	873	612	85	1472	1269	124	2054	1952
8	241	NA	47	889	629	86	1487	1286	125	2069	1969
9	259	NA	48	905	645	87	1502	1303	126	2084	1987
10	278	76	49	920	661	88	1517	1321	127	2099	2005
11	296	88	50	936	678	89	1532	1338	128	2113	2023
12	314	100	51	952	694	90	1547	1355	129	2128	2040
13	332	113	52	967	711	91	1562	1373	130	2143	2058
14	349	126	53	983	727	92	1577	1390	131	2158	2076
15	367	140	54	998	744	93	1592	1407	132	2172	2094
16	384	153	55	1014	760	94	1607	1425	133	2187	2111
17	401	167	56	1029	777	95	1623	1442	134	2202	2129
18	418	181	57	1045	793	96	1637	1459	135	2217	2147
19	435	195	58	1060	810	97	1652	1477	136	2231	2165
20	452	209	59	1076	827	98	1667	1494	137	2246	2183
21	469	224	60	1091	844	99	1682	1512	138	2261	2201
22	486	238	61	1106	860	100	1697	1529	139	2275	2218
23	503	253	62	1122	877	101	1712	1547	140	2290	2236
24	519	268	63	1137	894	102	1727	1564	141	2305	2254
25	536	283	64	1153	911	103	1742	1582	142	2320	2272
26	552	298	65	1168	928	104	1757	1599	143	2334	2290
27	569	313	66	1183	944	105	1772	1617	144	2349	2308
28	585	328	67	1199	961	106	1787	1634	145	2364	2326
29	602	343	68	1214	978	107	1802	1652	146	2378	2344
30	618	359	69	1229	995	108	1817	1669	147	2393	2361
31	634	374	70	1244	1012	109	1832	1687	148	2408	2379
32	650	389	71	1260	1029	110	1847	1704	149	2422	2397
33	667	405	72	1275	1046	111	1861	1722	150	2437	2415
34	683	421	73	1290	1063	112	1876	1740	151	2452	2433
35	699	436	74	1305	1080	113	1891	1757	152	2466	2451
36	715	452	75	1321	1097	114	1906	1775	153*)	NA	2469
37	731	468	76	1336	1114	115	1921	1793			
38	747	484	77	1351	1131	116	1936	1810	*) no	te 2 in ⊦	1.2.5

Table H.2.4-1: pass fail limits

NOTE 1: The first column is the number of errors (ne = number of NACK + statDTX)

NOTE 2: The second column is the number of samples for the pass limit ( $ns_p$ , ns=Number of Samples= number of NACK + statDTX + ACK)

NOTE 3: The third column is the number of samples for the fail limit (ns<sub>f</sub>)

#### H.2.5 Pass fail decision rules

The pass fail decision rules apply for a single test, comprising one component in the test vector. The overall Pass /Fail conditions are defined in clause H.2.6and H.2A.6

Having observed 0 errors, pass the test at	67+ samples,	otherwise continue
Having observed 1 error, pass the test at	95+ otherwise continue	
Having observed 2 errors, pass the test at	119+ samples, fail the test at 2- samples,	otherwise continue
	Etc. etc.	
Having observed 151 errors, pass the test at 2	2452+ samples, fail the test at 2433- samples,	otherwise continue
Having observed 152 errors, pass the test at 2	2466+ samples, fail the test at 2451- samples.	
Where x+ means: x or more, x- means x o	or less	

NOTE 1: an ideal DUT passes after 67 samples. The maximum test time is 2466 samples.

NOTE 2: It is allowed to deviate from the early decision concept by postponing the decision (pass/fail or continue). Postponing the decision to or beyond the end of Table H.2.4-1 requires a pass fail decision against the test limit: pass the DUT for ER<0.0618, otherwise fail.

## Annex I: Void

# Annex J (normative): Test applicability per permitted test method

This annex describes, per test requirement, the permitted test methodologies as a function of DUT antenna configuration.

Table J-1: Test case applicability per permitted test method
Table 0 1. rest base applicability per permitted test method

Clause	No DUT antenna configuration declaration	DUT antenna configuration declaration		
		Configuration 1	Configuration 2	Configuration 3
		(one antenna panel with D ≤	(More than one antenna	(Any phase
		5 cm active at any one time)	panel D ≤ 5 cm without	coherent
		, ,	phase coherency between	antenna panel
			panels active at any one time)	of any size)
6.5.1 Occupied	IFF	DFF, DFF simplification,	DFF, DFF simplification, IFF,	IFF
bandwidth		IFF, NFTF	NFTF	
6.5.2.1	IFF	DFF, DFF simplification,	DFF, DFF simplification, IFF,	IFF
Spectrum		IFF, NFTF	NFTF	
Emission Mask				
6.5.2.3	IFF	DFF, DFF simplification,	DFF, DFF simplification, IFF,	IFF
Adjacent		IFF, NFTF	NFTF	
leakage ratio				
7.5 Adjacent	IFF	DFF, DFF simplification,	DFF, DFF simplification, IFF,	IFF
Channel		IFF, NFTF	NFTF	
Selectivity				
7.6.2 In-band	IFF	DFF, DFF simplification,	DFF, DFF simplification, IFF,	IFF
Blocking		IFF, NFTF	NFTF	
NOTE: D = DL	JT radiating aperture of	eclared by UE vendor.		

## Annex K (normative): EIRP, TRP, and EIS measurement procedures

Editor's Note: The measurement procedures are applicable only for single-carrier test cases

Annex K defines the EIRP, TRP, and EIS measurement procedures which includes Tx and Rx beam peak direction search, spherical coverage procedures and TRP procedures for the permitted testing methodologies defined in [5].

## K.1 Direct far field (DFF)

#### K.1.1 TX beam peak direction search

This Tx beam peak search procedure applies to DUTs with and without beam correspondence. The TX beam peak direction is found with a 3D EIRP scan (separately for each orthogonal downlink polarization). The TX beam peak direction search grid points for this single grid approach are defined in Annex M.2.1. Alternatively, a coarse and fine grid approach could be used according to the definition in Annex M.2.2.

The beam peak searches shall be performed for every test frequency range by default unless the device manufacturer explicitly declares that the beam peak at the mid test frequency range is applicable for the remaining (low, high) test frequency ranges. Beam peak search results cannot be re-used across different bands that do not overlap. Beam peak search results can be re-used from bands that completely contain the target bands if explicitly declared with a declaration.

A beam peak search shall be performed for every intra-band contiguous combination and CA BW class by default unless the device manufacturer explicitly declares that the beam peak for a reference (frequency band, CBW) or (frequency band combination, CA BW class) is applicable for a group of other intra-band contiguous combinations and CA BW classes.

The beam peak searches shall be performed for every modulation by default unless the device manufacturer explicitly declares that the beam peak at the QPSK modulation is applicable for the remaining 16QAM and 64QAM modulations.

The beam peak searches shall be performed for every waveform by default unless the device manufacturer explicitly declares that the beam peak from one waveform is applicable for the other waveform.

The measurement procedure includes the following steps:

- 1) Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- 2) Position the DUT in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3].
- Connect the SS (System Simulator) with the DUT through the measurement antenna with Pol<sub>Link</sub>=θ polarization to form the TX beam towards the measurement antenna. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE TX beam selection to complete.
- 4) Send continuously uplink power control "up" commands in every uplink scheduling information to the UE; allow at least 200 msec starting from the first TPC Command in this step for the UE to reach P<sub>UMAX</sub> level. Allow at least BEAM\_SELECT\_WAIT\_TIME (Note 1) for the UE Tx beam selection to complete.
- 5) For beam correspondence, DUT refines its TX beam toward that direction depending on DUT's beam correspondence capability which shall match OEM declaration: if DUT's beam correspondence capability *beamCorrespondenceWithoutUL-BeamSweeping* is supported, then DUT autonomously chooses the corresponding TX beam for PUSCH transmission using downlink reference signals to transmit in the direction of the incoming DL signal, which is based on beam correspondenceWithoutUL-BeamSweeping is not present, then DUT's beam correspondence capability *beamCorrespondenceWithoutUL-BeamSweeping* is not present, then DUT chooses the TX beam for PUSCH transmission which is based on beam correspondence with relying on both DL measurements on downlink reference signals and network-assisted uplink beam sweeping (NOTE 2).

- 6) SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 7) Measure the mean power  $P_{meas}$  (Pol<sub>Meas</sub>= $\theta$ , Pol<sub>Link</sub>= $\theta$ ) of the modulated signal arriving at the power measurement equipment (such as a spectrum analyser, power meter, or gNB emulator).
- Calculate EIRP (Pol<sub>Meas</sub>=θ, Pol<sub>Link</sub>=θ) by adding the composite loss of the entire transmission path for utilized signal path, L<sub>EIRP,θ</sub>, and frequency to the measured power P<sub>meas</sub>(Pol<sub>Meas</sub>=θ, Pol<sub>Link</sub>=θ).
- 9) Measure the mean power  $P_{meas}$  (Pol<sub>Meas</sub>= $\phi$ , Pol<sub>Link</sub>= $\theta$ ) of the modulated signal arriving at the power measurement equipment.
- 10)Calculate EIRP (Pol<sub>Meas</sub>= $\phi$ , Pol<sub>Link</sub>= $\theta$ ) by adding the composite losses of the entire transmission path for utilized signal path, L<sub>EIRP, $\phi$ </sub>, and frequency to the measured power P<sub>meas</sub> (Pol<sub>Meas</sub>= $\phi$ , Pol<sub>Link</sub>= $\theta$ ).
- 11)Calculate total EIRP(Pol<sub>Link</sub>= $\theta$ ) = EIRP(Pol<sub>Meas</sub>= $\theta$ , Pol<sub>Link</sub>= $\theta$ ) + EIRP(Pol<sub>Meas</sub>= $\phi$ , Pol<sub>Link</sub>= $\theta$ ).
- 12)SS deactivates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.3.
- 13)Connect the SS (System Simulator) with the DUT through the measurement antenna with Pol<sub>Link</sub>= $\phi$  polarization to form the TX beam towards the measurement antenna. Allow at least BEAM\_SELECT\_WAIT\_TIME for the UE TX beam selection to complete.
- 14) Advance to the next grid point and repeat steps 3 through 13 until measurements within zenith range  $0^{\circ} \le \theta \le 90^{\circ}$  have been completed
- 15)After the measurements within zenith range  $0^{\circ} \le \theta \le 90^{\circ}$  have been completed and
  - a) if the re-positioning concept is applied to the TX test cases, position the device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] for the Alignment Option selected in Step 1. For the TX beam peak search in the second hemisphere, perform steps 3 through 14 for the range of zenith angles 90°<θ≤0°.</li>
  - b) if the re-positioning concept is not applied to the TX test cases, continue steps 3 through 14 for the range of zenith angles 90°<θ≤180°</p>

For beam correspondence capability *beamCorrespondenceWithoutUL-BeamSweeping* is not present, the above step 5) can be further clarified as following sub-steps:

- 5.1) DUT uses downlink reference signals to select proper RX beam and uses autonomous beam correspondence to select the TX beam.
- 5.2) SS configures M=8 SRS resources to DUT, with the field *spatialRelationInfo* omitted and the field *usage* set as 'beamManagement'. In case DUT supports less than 8 SRS resources, SS configures the number of SRS resources according to the maximum number of SRS resources indicated by UE capability signalling. Additionally, for codebook based PUSCH transmission, SS configures a semi-persistent SRS resource set with the field *usage* as 'codebook'.
- 5.3) Based on the TX beam autonomously selected by DUT, DUT chooses TX beams to transmit SRS-resources configured by SS.
- 5.4) Based on measurement of the received *beamManagement* SRS, SS chooses the best SRS beam and, if needed, updates the spatial relation information between the semi-persistent *codebook* SRS resources and the SS selected *beamManagement* SRS resource in the activation MAC CE of the semi-persistent SRS resource. The SS indicates in the SRS Resource Indicator (SRI) field in the scheduling grant for PUSCH, if present, the SRS resource within the semi-persistent SRS resource set whose spatial relation is linked to the best detected SRS beam.
- 5.5) DUT transmits PUSCH corresponding to the SRS resource indicated by the SRI.

The TX beam peak direction is where the maximum total component of EIRP(Pol<sub>Link</sub>= $\theta$ ) or EIRP(Pol<sub>Link</sub>= $\phi$ ) is found.

NOTE 1: The default value for BEAM\_SELECT\_WAIT\_TIME = 3 sec for all applicable Tx and Rx test cases. The BEAM\_SELECT\_WAIT\_TIME represents a default minimum wait time period required to complete beam selection process at a single position before start of measurement. For a particular EUT, if it is known/determined that a lower wait time than default value is enough to complete beam selection process, then such a lower value may be used by the Test system to achieve test time optimization.

NOTE 2: This is used for beam correspondence.

#### K.1.2 RX beam peak direction search

The RX beam peak direction is found with a 3D EIS scan (separately for each orthogonal downlink polarization). The RX beam peak direction search grid points for this single grid approach are defined in Annex M.2.1. Alternatively, a coarse and fine grid approach could be used according to the definition in Annex M.2.4.

The beam peak searches shall be performed for every test frequency range by default unless the device manufacturer explicitly declares that the beam peak at the mid test frequency range is applicable for the remaining (low, high) test frequency ranges. Beam peak search results cannot be re-used across different bands that do not overlap. Beam peak search results can be re-used from bands that completely contain the target bands if explicitly declared with a declaration.

A beam peak search shall be performed for every intra-band contiguous combination and CA BW class by default unless the device manufacturer explicitly declares that the beam peak for a reference (frequency band, CBW) or (frequency band combination, CA BW class) is applicable for a group of other intra-band contiguous combinations and CA BW classes.

The beam peak searches shall be performed for every modulation by default unless the device manufacturer explicitly declares that the beam peak at the QPSK modulation is applicable for the remaining 16QAM and 64QAM modulations.

The beam peak searches shall be performed for every waveform by default unless the device manufacturer explicitly declares that the beam peak from one waveform is applicable for the other waveform.

The measurement procedure includes the following steps:

- 1) Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- 2) Position the DUT in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3].
- Connect the SS (System Simulator) with the DUT through the measurement antenna with Pol<sub>Link</sub>=θ polarization to form the RX beam towards the measurement antenna. Allow at least BEAM\_SELECT\_WAIT\_TIME NOTE
   for the UE RX beam selection to complete.
- 4) Determine EIS( $Pol_{Meas}=\theta$ ,  $Pol_{Link}=\theta$ ) for  $\theta$ -polarization, i.e., by sweeping the power level for the  $\theta$ -polarization, at which the throughput exceeds the requirements for the specified reference measurement channel. The downlink power step size shall be no more than 0.2 dB when the RF power level is near the sensitivity level.
- 5) Connect the SS (System Simulator) with the DUT through the measurement antenna with Pol<sub>Link</sub>= ¢ polarization to form the RX beam towards the measurement antenna. Allow at least BEAM\_SELECT\_WAIT\_TIME for the UE RX beam selection to complete.
- 6) Determine EIS(Pol<sub>Meas</sub>=φ, Pol<sub>Link</sub>=φ) for φ-polarization, i.e., by sweeping the power level for the φ-polarization, at which the throughput exceeds the requirements for the specified reference measurement channel. The downlink power step size shall be no more than 0.2 dB when the RF power level is near the sensitivity level.
- 7) Advance to the next grid point and repeat steps 3 through 6 until measurements within zenith range  $0^{\circ} \le \theta \le 90^{\circ}$  have been completed
- 8) After the measurements within zenith range  $0^{\circ} \le \theta \le 90^{\circ}$  have been completed and
  - a) if the re-positioning concept is applied to the RX test cases, position the device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] for the Alignment Option selected in Step 1. For the RX beam peak search in the second hemisphere, perform steps 3 through 6 for the range of zenith angles 90°<θ≤0°.</li>

- b) If the re-positioning concept is not applied to the RX test cases, continue steps 3 through 6 for the range of zenith angles 90°<θ≤180°</p>
- 9) Calculate the resulting "averaged EIS" as:

averaged EIS =  $2*[1/\text{EIS}(\text{Pol}_{\text{Meas}}=\theta, \text{Pol}_{\text{Link}}=\theta) + 1/\text{EIS}(\text{Pol}_{\text{Meas}}=\phi, \text{Pol}_{\text{Link}}=\phi)]^{-1}$ 

The RX beam peak direction is where the minimum "averaged EIS" is found.

#### K.1.3 Peak EIRP measurement procedure

This section describes EIRP measurement procedure for a chosen  $Pol_{Link}$  of  $\theta$  or  $\phi$ 

The TX beam peak direction is where the maximum total component of EIRP is found, including the respective polarization of the measurement antenna used to form the TX beam, according to K.1.1.

The measurement procedure includes the following steps:

- 1) Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- 2) If the re-positioning concept is not applied to the TX test cases, position the device in DUT Orientation 1. If the re-positioning concept is applied to the TX test cases,
  - a) position the device in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $0^{\circ} \le \theta \le 90^{\circ}$  for the alignment option selected in step 1
  - b) position the device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $90^{\circ} < \theta \le 180^{\circ}$  for DUT Orientation 1 for the alignment option selected in step 1.
- 3) Connect the SS (System Simulator) with the DUT through the measurement antenna with polarization reference Pol<sub>Link</sub> to form the TX beam towards the TX beam peak direction and respective polarization. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE TX beam selection to complete.
- 4) SS activates the UE Beamlock Function (UBF) by performing the procedure as specified in TS 38.508-1 [10] clause 4.9.2 using condition Tx only.
- 5) Measure the mean power  $P_{meas}$  ( $Pol_{Meas}=\theta$ ,  $Pol_{Link}$ ) of the modulated signal arriving at the power measurement equipment (such as a spectrum analyser, power meter, or gNB emulator).
- 6) Calculate EIRP(Pol<sub>Meas</sub>= $\theta$ , Pol<sub>Link</sub>) by adding the composite loss of the entire transmission path for utilized signal path, L<sub>EIRP, $\theta$ </sub>, and frequency to the measured power P<sub>meas</sub> (Pol<sub>Meas</sub>= $\theta$ , Pol<sub>Link</sub>).
- 7) Measure the mean power  $P_{meas}$  (Pol<sub>Meas</sub>= $\phi$ , Pol<sub>Link</sub>) of the modulated signal arriving at the power measurement equipment.
- Calculate EIRP(Pol<sub>Meas</sub>=φ, Pol<sub>Link</sub>) by adding the composite losses of the entire transmission path for utilized signal path, L<sub>EIRP,φ</sub> and frequency to the measured power P<sub>meas</sub> (Pol<sub>Meas</sub>=φ, Pol<sub>Link</sub>)
- 9) Calculate the resulting "total EIRP(Pol<sub>Link</sub>)", for the chosen Pol<sub>Link</sub> of  $\theta$  or  $\phi$  as follows:

 $total EIRP (Pol_{Link}) = EIRP(Pol_{Meas}=\theta, Pol_{Link}) + EIRP(Pol_{Meas}=\phi, Pol_{Link})$ 

#### K.1.4 Peak EIS measurement procedure

This section describes EIS measurement procedure. The RX beam peak direction is where the minimum EIS is found according to K.1.2.

The measurement procedure includes the following steps:

1) Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.

- 2) If the re-positioning concept is not applied to the RX test cases, position the device in DUT Orientation 1. If the re-positioning concept is applied to the RX test cases
  - a) position the device in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $0^{\circ} \le \theta \le 90^{\circ}$  for the alignment option selected in step 1
  - b) position the device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $90^{\circ} < \theta \le 180^{\circ}$  for DUT Orientation 1 for the alignment option selected in step 1.
- Connect the SS (System Simulator) with the DUT through the measurement antenna with Pol<sub>Link</sub>=θ polarization to form the RX beam towards the RX beam peak direction. Allow at least BEAM\_SELECT\_WAIT\_TIME (NOTE 1) for the UE RX beam selection to complete.
- 4) Determine EIS(Pol<sub>Meas</sub>= $\theta$ , Pol<sub>Link</sub>= $\theta$ ) for  $\theta$ -polarization, i.e., the power level for the  $\theta$ -polarization at which the throughput exceeds the requirements for the specified reference measurement channel. The downlink power step size shall be no more than 0.2 dB when the RF power level is near the sensitivity level.
- 6) Determine EIS(Pol<sub>Meas</sub>=φ, Pol<sub>Link</sub>=φ) for φ-polarization, i.e., the power level for the φ-polarization at which the throughput exceeds the requirements for the specified reference measurement channel. The downlink power step size shall be no more than 0.2 dB when the RF power level is near the sensitivity level.
- 7) Calculate the resulting averaged EIS as:

 $EIS = 2*[1/EIS(Pol_{Mes}=\theta, Pol_{Link}=\theta) + 1/EIS(Pol_{Meas}=\phi, Pol_{Link}=\phi)]^{-1}$ 

#### K.1.5 EIRP spherical coverage

The EIRP results from the TX beam peak search procedures of K.1.1, using the minimum number of grid points as described in Annex M.2.1 can be re-used for EIRP spherical coverage.

In case a coarse beam peak grid is used for TX beam peak search, using the minimum number of grid points defined in Annex M.3.1.1, the EIRP results can be re-used for EIRP spherical coverage.

In case a separate test is performed for EIRP spherical coverage, the procedure as per K.1.3 should be followed using the minimum number of grid points defined in Annex M.3.1.1 for spherical coverage.

The EIRP<sub>target-CDF</sub> is then obtained from the Cumulative Distribution Function (CDF) computed using maximum(EIRP(Pol<sub>Link</sub>= $\theta$ ), EIRP(Pol<sub>Link</sub>= $\phi$ )) for all grid points. When using constant step size measurement grids, a theta-dependent correction shall be applied, i.e., the PDF probability contribution for each measurement point is scaled by sin( $\theta$ ) or the normalized Clenshaw-Curtis weights W( $\theta$ )/W(90°), introduced in Section M.4.2.1, to account for the denser grid point distribution near the poles. In case of Clenshaw-Curtis weights, when just a single measurement at the poles is performed, the PDF probability contributions need to be scaled by M\*W( $\theta$ )/W( $\theta$ =90°) to account for the M longitudes at those two grid points. When using constant density grids, these corrections are not needed.

#### K.1.6 EIS spherical coverage

The EIS results from the RX beam peak search procedures of K.1.2, using the minimum number of grid points as described in Annex M.2.2 can be re-used for EIS spherical coverage.

In case a coarse beam peak grid is used for RX beam peak search with an EIS metric, using the minimum number of grid points defined in Annex M.3.2.1, the EIS results can be re-used for EIS spherical coverage.

In case a separate test is performed for spherical coverage, the procedure K.1.4 should be followed using the minimum number of grid points defined in Annex M.3.2.1 for spherical coverage.

The  $EIS_{target-CDF}$  is then obtained from the Cumulative Distribution Function (CDF) computed using averaged EIS for all grid points. When using constant step size measurement grids, a theta-dependent correction shall be applied, i.e., the

PDF probability contribution for each measurement point is scaled by  $\sin(\theta)$  or the normalized Clenshaw-Curtis weights  $W(\theta)/W(90^\circ)$ , introduced in Section M.4.2.1, to account for the denser grid point distribution near the poles. In case of Clenshaw-Curtis weights, when just a single measurement at the poles is performed, the PDF probability contributions need to be scaled by  $M^*W(\theta)/W(\theta=90^\circ)$  to account for the M longitudes at those two grid points. When using constant density grids, these corrections are not needed.

#### K.1.7 TRP measurement procedure

The minimum number of measurement points for TRP measurement grid is outlined in Annex M.4.

The measurement procedure includes the following steps:

- 1) Select any of the three Alignment Options (1, 2, or 3) from Tables J.2-1 through J.2-3 [3] to mount the DUT inside the QZ.
- 2) If the re-positioning concept is not applied to the TX test cases, position the device in DUT Orientation 1. If the re-positioning concept is applied to the TX test cases
  - a) position the device in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $0^{\circ} \le \theta \le 90^{\circ}$  for the alignment option selected in step 1
  - b) Position de device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range 90°<θ≤180° for DUT Orientation 1 for the alignment option selected in step 1.</p>
- 3) Connect the SS with the DUT through the downlink antenna with desired polarization reference Pol<sub>Link</sub> to form the TX beam towards the desired TX beam direction and respective polarization.
- 4) Lock the beam toward that direction and polarization for the entire duration of the test. Send continuously uplink power control "up" commands in every uplink scheduling information to the UE.
- 5) For each measurement point, measure  $P_{meas}(Pol_{Meas}=\theta, Pol_{Link})$  and  $P_{meas}(Pol_{Meas}=\phi, Pol_{Link})$ . The angle between the measurement antenna and the DUT ( $\theta_{Meas}, \phi_{Meas}$ ) is achieved by rotating the measurement antenna and the DUT (based on system architecture).
- 6) Calculate EIRP(Pol<sub>Meas</sub>=θ, Pol<sub>Link</sub>) and EIRP(Pol<sub>Meas</sub>=φ, Pol<sub>Link</sub>) by adding the composite loss of the entire transmission path for utilized signal paths, L<sub>EIRP,θ</sub>, L<sub>EIRP,φ</sub> and frequency to the respective measured powers P<sub>meas</sub>.
- The TRP value for the uniform measurement grid is calculated using the TRP integration approaches outlined in Annex M.4.2. The TRP value for the constant density grid is calculated using the TRP integration formula in Annex M.4.3.

#### K.1.8 Blocking measurement procedure

The RX beam peak direction is where the minimum EIS is found according to K.1.2.

The measurement procedure includes the following steps:

- 1) Select any of the three Alignment Options (1, 2, or 3) from Tables C.2-1 through C.2-3 to mount the DUT inside the QZ.
- 2) If the re-positioning concept is not applied to the RX test cases, position the device in DUT Orientation 1. If the re-positioning concept is applied to the RX test cases
  - a) position the device in DUT Orientation 1 from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $0^{\circ} \le \theta \le 90^{\circ}$  for the alignment option selected in step 1
  - b) position the device in DUT Orientation 2 (either Options 1 or 2) from Tables J.2-1 through J.2-3 [3] if the maximum beam peak direction is within zenith angular range  $90^{\circ} < \theta \le 180^{\circ}$  for DUT Orientation 1 for the alignment option selected in step 1.
- 3) Establish a connection between the DUT and the SS with the downlink signal applied to the  $\theta$ -polarization of the measurement antenna

- 4) Position the UE so that the beam is formed towards the measurement antenna in the RX beam peak direction.
- 5) Apply a signal with the specified reference measurement channel on the θ-polarization, setting the power level of the signal 3dB below the EIS level stated in the requirement.
- 6) Apply the blocking signal with the same polarization and coming from the same direction as the downlink signal. Set the power level of the blocking signal 3dB below the level stated in the requirement.
- 7) Measure the throughput of the downlink signal on the  $\theta$ -polarization.
- 8) Switch the downlink and blocking signal to the  $\varphi$ -polarization of the measurement antenna.
- 9) Repeat steps 3 to 7 on the  $\varphi$ -polarization.
- 10)Compare the results for both the  $\theta$ -polarization and  $\varphi$ -polarization against the requirement. If both results meet the requirements, pass the UE.

#### K.1.9 Beam Correspondence tolerance procedure

Editor's Note: The side conditions for downlink reference signals SSB and CSI-RS in beam correspondence tolerance test are FFS.

This beam correspondence tolerance procedure applies to the DUT with beam correspondence capability *beamCorrespondenceWithoutUL-BeamSweeping* not present (which shall match OEM declaration), such that DUT relies on uplink beam sweeping to fulfil the minimum peak EIRP and spherical coverage requirements.

The measurement procedure includes the following steps for each of the points in the grid:

- Follow the test procedures specified in subclause K.1.5 with uplink beam sweeping disabled, obtain total EIRP<sub>1</sub>(Pol<sub>Link</sub>=θ) and total EIRP<sub>1</sub>(Pol<sub>Link</sub>=φ). EIRP<sub>1</sub> is calculated by EIRP<sub>1</sub> = maximum(EIRP<sub>1</sub>(Pol<sub>Link</sub>=θ), EIRP<sub>1</sub>(Pol<sub>Link</sub>=φ)).
- Follow the test procedures specified in subclause K.1.5, with uplink beam sweeping enabled (SS does not configure the *spatialRelationInfo* to DUT) during DUT TX beam refinement, obtain total EIRP<sub>2</sub>(Pol<sub>Link</sub>=θ) and total EIRP<sub>2</sub>(Pol<sub>Link</sub>=φ). EIRP<sub>2</sub> is calculated by EIRP<sub>2</sub> = maximum(EIRP<sub>2</sub>(Pol<sub>Link</sub>=θ), EIRP<sub>2</sub>(Pol<sub>Link</sub>=φ)).
- 3) Calculate the  $\Delta EIRP_{BC} = EIRP_2 EIRP_1$ .

The  $\Delta EIRP_{target-CDF}$  is then obtained from the Cumulative Distribution Function (CDF) computed using  $\Delta EIRP_{BC}$  for each of all top N<sup>th</sup> percentile of the EIRP<sub>2</sub> measurement points in the grid. When using constant step size measurement grids, a theta-dependent correction shall be applied, i.e., the PDF probability contribution for each measurement point is scaled by  $sin(\theta)$  or the normalized Clenshaw-Curtis weights W( $\theta$ )/W(90°), introduced in Section M.4.2.1.

NOTE:  $\Delta$ EIRP<sub>BC</sub> is introduced for beam correspondence tolerance based on two EIRP measurements (EIRP<sub>1</sub> and EIRP<sub>2</sub>). EIRP<sub>1</sub> is the measured total EIRP based on the beam which DUT chooses autonomously (corresponding beam) to transmit in the direction of the incoming DL signal, which is based on beam correspondence without relying on UL beam sweeping. EIRP<sub>2</sub> is the measured total EIRP based on the beam yielding highest EIRP in a given direction, which is based on beam correspondence with relying on UL beam sweeping.  $\Delta$ EIRP<sub>BC</sub> shall be calculated over the link angles spanning a subset of the spherical coverage grid points which are corresponding to the top N<sup>th</sup> percentile of the EIRP<sub>2</sub> measurement points in the grid, where the value of N is according to EIRP spherical coverage requirement of DUT's power class defined in TS 38.101-2 [3] clause 6.2.1, e.g., N=50 for power class 3 DUT.

## K.2 Direct far field (DFF) simplification

#### K.2.1 TX beam peak direction search

Same measurement procedure as in clause K.1.1.

## K.2.2 RX beam peak direction search

Same measurement procedure as in clause K.1.2.

#### K.2.3 Peak EIRP measurement procedure

Same measurement procedure as in clause K.1.3.

#### K.2.4 Peak EIS measurement procedure

Same measurement procedure as in clause K.1.4.

#### K.2.5 EIRP spherical coverage

Same measurement procedure as in clause K.1.5.

#### K.2.6 EIS spherical coverage

Same measurement procedure as in clause K.1.6.

#### K.2.7 TRP measurement procedure

Same measurement procedure as in clause K.1.7.

#### K.2.8 Blocking measurement procedure

Same measurement procedure as in clause K.1.8.

## K.3 Indirect far field (IFF)

#### K.3.1 TX beam peak direction search

Same measurement procedure as in clause K.1.1.

#### K.3.2 RX beam peak direction search

Same measurement procedure as in clause K.1.2.

#### K.3.3 Peak EIRP measurement procedure

Same measurement procedure as in clause K.1.3.

#### K.3.4 Peak EIS measurement procedure

Same measurement procedure as in clause K.1.4.

#### K.3.5 EIRP spherical coverage

Same measurement procedure as in clause K.1.5.

#### K.3.6 EIS spherical coverage

Same measurement procedure as in clause K.1.6.

#### K.3.7 TRP measurement procedure

Same measurement procedure as in clause K.1.7.

#### K.3.8 Blocking measurement procedure

Same measurement procedure as in clause K.1.8.

## K.4 Near field to far field transform (NFTF)

#### K.4.1 TX beam peak direction search

The TX beam peak direction is found with a 3D EIRP scan (separately for each orthogonal polarization) with a grid that is TBD. The TX beam peak direction is where the maximum total component of EIRP is found.

FFS

#### K.4.2 RX beam peak direction search

Not applicable for NFTF method.

#### K.4.3 Peak EIRP measurement procedure

- Connect the SS (System Simulator) to the DUT through the measurement antenna with polarization reference Pol<sub>Meas</sub> to form the TX beam towards the previously determined TX beam peak direction and respective polarization.
- 2) Lock the beam toward that direction for the entire duration of the test.
- 3) Perform a 3D pattern measurement (amplitude and phase) with the DUT sending a modulated signal.
- 4) Determine the EIRP for both polarization towards the TX beam peak direction by using a Near Field to Far Field transform.
- 5) Calculate total  $EIRP = EIRP_{\theta} + EIRP_{\phi}$

#### K.4.4 Peak EIS measurement procedure

Not applicable for NFTF method.

#### K.4.5 EIRP spherical coverage

Same measurement procedure as in clause K.1.5.

## K.4.6 EIS spherical coverage

Not applicable for NFTF method.

#### K.4.7 TRP measurement procedure

The minimum number of measurement points for TRP measurement grid is outlined in Annex M.4.

The measurement procedure includes the following steps:

- 1) Connect the SS to the DUT through the measurement antenna with polarization reference Pol<sub>Meas</sub> to form the TX beam towards the previously determined TX beam peak direction and respective polarization.
- 2) Lock the beam toward that direction for the entire duration of the test.
- 3) Perform a 3D pattern measurement (amplitude and phase) with the DUT sending a modulated signal.
- 4) For each measurement point on the grid, determine the EIRP for both polarization by using a Near Field to Far Field transform.

5) The TRP value for the constant step size measurement grids are calculated using the TRP integration approaches outlined in Annex M.4.2. The TRP value for the constant density grid is calculated using the TRP integration formula in Annex M.4.3.

#### K.4.8 Blocking measurement procedure

Not applicable for NFTF method.

Annex L (normative): Void

## Annex M:(normative) Measurement grids

This appendix describes the assumptions and definition of the minimum number of measurement grid points for various grid types. Further details can be found in [5].

A total of three measurement grids are considered:

- Beam Peak Search Grid: using this grid, the TX and RX beam peak direction will be determined. 3D EIRP scans are used to determine the TX beam peak direction and 3D Throughput/RSRP/EIS scans for RX beam peak directions.
- Spherical Coverage Grid: using this grid, the CDF of the EIRP/EIS distribution in 3D is calculated to determine the spherical coverage performance.
- TRP Measurement Grid: using this grid, the total power radiated by the DUT in the TX beam peak direction is determined by integrating the EIRP measurements taken on the sampling grid.

## M.1 Grid Types

Two different measurement grid types are considered:

- The constant step size grid type has the azimuth and elevation angles uniformly distributed as in the examples illustrated in Figures M.1-1 in 2D and M.1-2 in 3D.

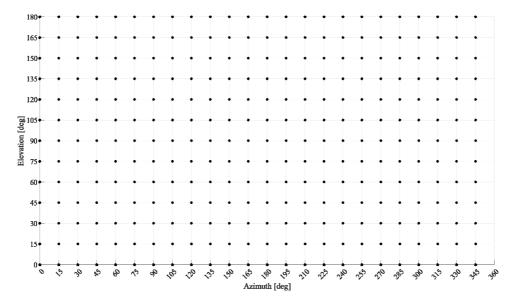


Figure M.1-1: Distribution of measurement grid points in 2D for a constant step size grid with  $\Delta\theta=\Delta\phi=15^{\circ}$  (266 unique measurement points)

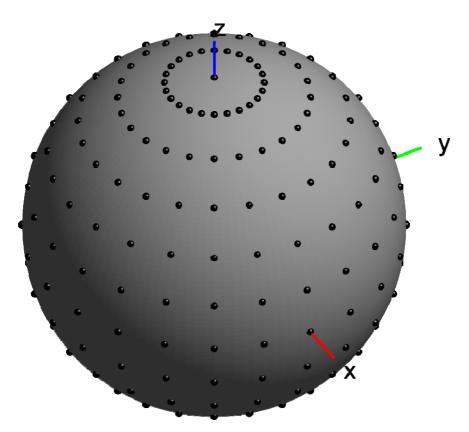


Figure M.1-2: Distribution of measurement grid points in 3D for a constant step size grid with  $\Delta\theta=\Delta\phi=15^{\circ}$  (266 unique measurement points)

- Constant density grid types have measurement points that are evenly distributed on the surface of the sphere with a constant density as in the example illustrated in Figures M.1-3 in 2D and M.1-4 in 3D.

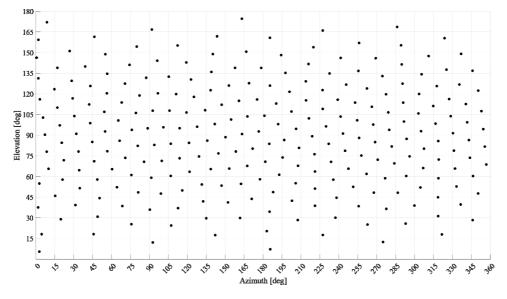


Figure M.1-3: Distribution of measurement grid points in 2D for a constant density grid with 266 unique measurement points

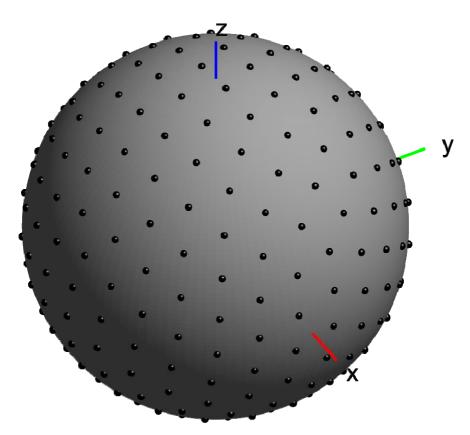


Figure M.1-4: Distribution of measurement grid points in 3D for a constant density grid type with 266 unique measurement points

## M.2 Beam Peak Search Grid

Editor's note: Other implementations are not precluded as far as the respective analysis are presented and included in this TS

#### M.2.1 UE Power classes

#### M.2.1.1 Power class 1 devices

In order to make a reasonable trade-off with measurement uncertainties, it is recommended to use for beam peak search the following measurement grids leading to a systematic error of "Beam Peak Search" of 0.7 dB:

- Constant density grid (using the charged particle implementation) with at least 3000 grid points.
- Constant step size grid with at least 4902 grid points, corresponding to an angular step size of 3.6°.

For better measurement uncertainties, finer measurement grids as shown in Table M.2.1.1-1 may be used. Choice of grids among these 2 types of grids is up to test system implementation.

Systematic Error of 'Beam Peak Search': Offset from Beam Peak at which CDF is 5%	Minimum Number of Unique Grid Points for Constant Step Size Grid	Minimum Number of Unique Grid Points for Constant Density Grid
0.3dB	10226 (2.5° step size)	7000
0.4dB	N/A	5000
0.5dB	7082 (3°step size)	4500
0.6dB	N/A	3500
0.7dB	4902 (3.6° step size)	3000

 Table M.2.1.1-1: Minimum number of unique grid points for sample systematic errors

#### M.2.1.2 Power class 2 devices

TBD

#### M.2.1.3 Power class 3 devices

In order to make a reasonable trade-off between measurement uncertainties, at least 800(constant density grid with charged particle implementation) or 1106 (constant step size grid) measurement grid points shall be used for beam peak search procedures. For better measurement uncertainties, finer measurement grids as shown below may be used. Choice of grids among these 2 types of grids is up to test system implementation.

# Table M.2.1.3-1: Minimum number of unique grid points for sample systematic errors (non-sparse antenna arrays)

Systematic Error of 'Beam Peak Search': Offset from Beam Peak at which CDF is 5%	Minimum Number of Unique Grid Points for Constant Step Size Grid	Minimum Number of Unique Grid Points for Constant Density Grid (charged particle implementation)
0.2dB	2522 (5° step size)	2000
0.3dB	1742 (6º step size)	1500
0.4dB	N/A	1000
0.5dB	1106 (7.5°step size)	800

#### M.2.1.4 Power class 4 devices

TBD

#### M.2.2 Coarse and fine measurement grids

The baseline beam peak search is based on a single and fine beam peak search grid to determine the TX/RX beam peak of the DUT in any given direction. This means that even in sectors where poor EIRP/EIS performance is observed, a very fine grid is used to search for the TX/RX beam peak.

An optimized approach, based on an initial coarse search followed by a subsequent fine search could reduce the number of beam peak search grid points significantly. The basis for this approach is to use a coarse grid with fewer number of points than the ones described in section M.2.1 in the first stage to identify candidate regions that contain the global beam peak and search for the global beam peak with the fine grid in the second stage with a minimum number of points described in section M.2.1.

As an example, Figure M.2.2-1 illustrates the coarse and fine measurement grid approach applied to TX beam search; while this illustration is for EIRP, it can easily be extended to RX beam peak search using EIS or throughput metrics For simplification purposes, 2D coarse and fine searches are illustrated but the concept can be extended to 3D easily. The UE is assumed to form a total of six beams in the 2D plane as illustrated on the left of Figure M.2.2-1. In the centre of Figure M.2.2-1, the 36 coarse beam peak search grid points in the 2D plane are illustrated. On the right, the grey circles on the respective antenna patterns illustrate the measured EIRP values towards each coarse grid point direction based on the respective beam steering directions. This illustration shows that the EIRP beam peak of the coarse search,

 $EIRP_{CSBP}$ , is found to be the peak of the orange beam while the global TX beam peak (red beam) was not identified due to the coarse sampling of the grid points.

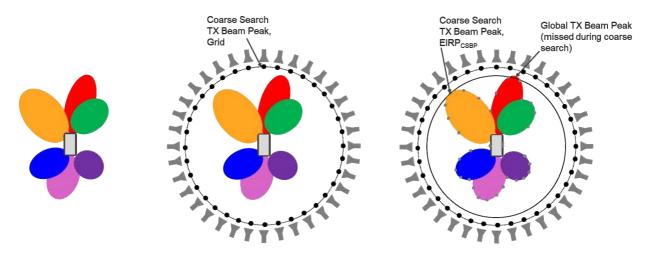


Figure M.2.2-1: Illustration of the Coarse Search Approach for TX Beam Peak Search. Left: Antenna Pattern assumptions in 2D, Centre: Coarse beam peak search grid points/discrete antenna measurement positions, Right: TX beam EIRP measurements per grid point

The proposed fine search approach is illustrated further in Figure M.2.2-2. A fine search region starting from the beam peak identified in the coarse search, EIRP<sub>CSBP</sub>, over a range of  $\Delta_{FS}$  is used to identify the regions that need to be investigated more closely with the fine search algorithm. The fine search range  $\Delta_{FS}$  is a function of the angular spacing of the coarse beam peak search grid as well as the beam width of the reference antenna pattern considered for smartphone UEs.

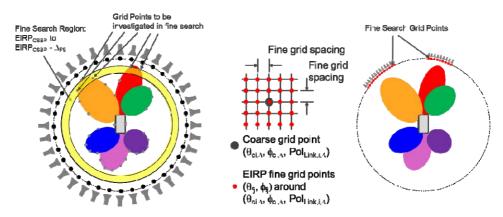


Figure M.2.2-2: Illustration of the fine beam peak search grid. Left: identify the measurement grid points that yielded EIRP values within the fine search region, right: placement of fine beam peak search grid points

Figure M.2.2-3 illustrates coarse and fine grids for constant step size measurement grids while Figure M.2.2-4 illustrates the same for constant density grid.

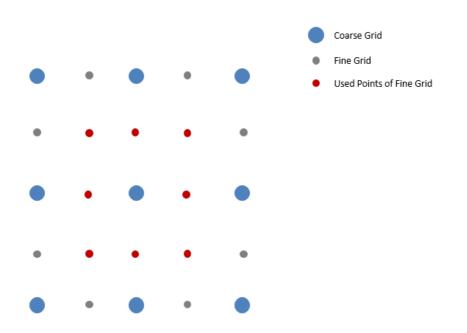


Figure M.2.2-3: Illustration: Coarse & Fine Constant Step Size Grids

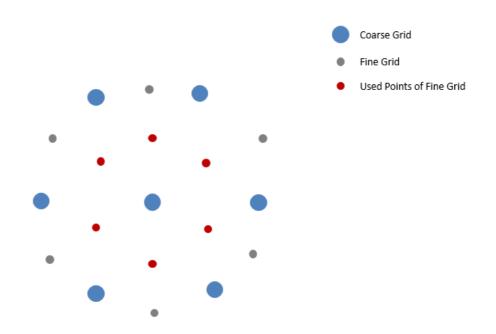


Figure M.2.2-4: Illustration: Coarse & Fine Constant Density Grids

The metric using a coarse & fine grid approach for the TX beam peak search is EIRP for both grids. For RX beam peak search either EIS or Throughput could be used for coarse grids while only EIS for fine grid,

### M.3 Spherical Coverage Grid

Editor's note: Other implementations are not precluded as far as the respective analysis are presented and included in this TS

### M.3.1 EIRP spherical coverage

#### M.3.1.1 UE Power classes

#### M.3.1.1.1 Power class 1 devices

In order to make a reasonable trade-off with measurement uncertainties, it is recommended to use the following recommendation in terms of min. number of grid points, standard deviation, and mean error for spherical coverage grids:

- constant density grid (using the charged particle implementation) with at least 200 grid points: standard deviation (MU element 'Influence of spherical coverage grid') of 0.05dB and 0.01dB Mean Error
- constant step size grid with at least 266 grid points: standard deviation (MU element 'Influence of spherical coverage grid') of 0.05dB and 0.01dB Mean Error

For better measurement uncertainties, finer measurement grids as shown in Tables M.3.1.1.1-1 and M.3.1.1.1-2 may be used. Choice of grids among these 2 types of grids is up to test system implementation.

There is no need to have the Tx beam peak placed on a measurement grid point.

For constant step size measurement grids, the CDF analyses require the PDFs to be scaled by sin(theta) or the normalized Clenshaw-Curtis weights  $W(\theta)/W(90^\circ)$ , introduced in Section M.4.2.1.

## Table M.3.1.1.1-1: Statistical results of EIRP<sub>85%CDF</sub> for the 12x12 antenna array for constant step size measurement grids and the beam peak oriented in completely random orientations.

Step Size [º]	Number of unique grid points	Std. Dev [dB]	Mean Error  [dB]
4.5	3122	0.02	0.00
10	614	0.03	0.00
12	422	0.04	0.01
15	266	0.05	0.01
20	146	0.07	0.02
22.5	114	0.09	0.04
30	62	0.11	0.06
36	42	0.15	0.12
45	26	0.19	0.19

Number of unique grid points	Std. Dev [dB]	Mean Error  [dB]
200	0.05	0.01
175	0.06	0.01
150	0.06	0.02
125	0.07	0.02
100	0.08	0.02
50	0.11	0.05
25	0.17	0.12
15	0.27	0.27

Table M.3.1.1.1-2: Statistical results of EIRP<sub>50%CDF</sub> for the 12x12 antenna array for constant density measurement grids and the beam peak oriented in completely random orientations.

#### M.3.1.1.2 Power class 2 devices

TBD

#### M.3.1.1.3 Power class 3 devices

In order to make a reasonable trade-off between measurement uncertainties, at least 200 (constant density grid with charged particle implementation) or 266 (constant step size grid) measurement grid points shall be used for EIRP spherical coverage procedure. For better measurement uncertainties, finer measurement grids as shown below may be used. Choice of grids among these 2 types of grids is up to test system implementation.

There is no need to have the Tx beam peak placed on a measurement grid point.

For constant step size measurement grids, the CDF analyses require the PDFs to be scaled by sin(theta) or the normalized Clenshaw-Curtis weights  $W(\theta)/W(90^\circ)$ , introduced in Section M.4.2.1.

# Table M.3.1.1.3-1: Statistical results of EIRP50%CDF for the 8x2 antenna array for constant density measurement grids (with charged particle implementation) and the beam peak oriented in completely random orientations errors (non-sparse antenna arrays)

Number of unique grid points	STD [dB]	Mean Error  [dB]
200	0.11	0.02
300	0.08	0.01
400	0.07	0.01
500	0.06	0.01

# Table M.3.1.1.3-2: Statistical results of EIRP50%CDF for the 8x2 antenna array for constant step size measurement grids and the beam peak oriented in completely random orientations errors (non-sparse antenna arrays)

Step Size [°]	Number of unique grid points	STD [dB]	Mean Error  [dB]
9	762	0.05	0.00
10	614	0.06	0.00
12	422	0.07	0.01
15	266	0.12	0.01

M.3.1.1.4 Power class 4 devices

TBD

## M.3.2 EIS spherical coverage

### M.3.2.1 UE Power classes

#### M.3.2.1.1 Power class 1 devices

In order to make a reasonable trade-off with measurement uncertainties, it is recommended to use the following recommendation in terms of min. number of grid points, standard deviation, and mean error for spherical coverage grids:

- constant density grid (using the charged particle implementation) with at least 200 grid points: standard deviation (MU element 'Influence of spherical coverage grid') of 0.05dB and 0.01dB Mean Error
- constant step size grid with at least 266 grid points: standard deviation (MU element 'Influence of spherical coverage grid') of 0.05dB and 0.01dB Mean Error
- the MU element 'Systematic error related to EIS spherical coverage' is the DL step size, i.e., 0.2dB.

Choice of grids among these 2 types of grids is up to test system implementation.

There is no need to have the Rx beam peak placed on a measurement grid point.

For constant step size measurement grids, the CCDF analyses require the PDFs to be scaled by sin(theta) or the normalized Clenshaw-Curtis weights  $W(\theta)/W(90^\circ)$ , introduced in Section M.4.2.1.

#### M.3.2.1.2 Power class 2 devices

TBD

#### M.3.2.1.3 Power class 3 devices

In order to make a reasonable trade-off between measurement uncertainties, at least 200 (constant density grid with charged particle implementation) or 266 (constant step size grid) measurement grid points shall be used for EIS spherical coverage procedure. For better measurement uncertainties, finer measurement grids as shown below may be used. Choice of grid(s) among these 2 types of grids is up to test system implementation.

There is no need to have the Rx beam peak placed on a measurement grid point.

For constant step size measurement grids, the CCDF analyses require the PDFs to be scaled by sin(theta) or the normalized Clenshaw-Curtis weights  $W(\theta)/W(90^\circ)$ , introduced in Section M.4.2.1.

# Table M.3.2.1.3-1: Statistical results of EIS50%CDF for the 8x2 antenna array for constant step size measurement grids and the beam peak oriented in completely random orientations errors (non-sparse antenna arrays)

		Step	Power o Size: itesimal	Step	Power o Size: 1dB	Ste	Power o Size: 5dB	Step	Power o Size: dB
Step Size [°]	Number of unique grid points	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]
6.0	1742	0.03	0.00	0.03	0.10	0.03	0.50	0.02	1.02
9.0	762	0.05	0.00	0.05	0.10	0.05	0.50	0.04	1.02
10.0	614	0.06	0.00	0.06	0.10	0.06	0.50	0.05	1.02
12.0	422	0.08	0.01	0.07	0.10	0.07	0.50	0.07	1.02
15.0	266	0.12	0.02	0.12	0.10	0.11	0.50	0.10	1.02

Table M.3.2.1.3-2: Statistical results of EIS50%CDF for the 8x2 antenna array for constant density measurement grids (with charged particle implementation) and the beam peak oriented in completely random orientations errors (non-sparse antenna arrays)

				DL Power Step Size: 0.5dB		DL Power Step Size: 1dB		
Number of unique grid points	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]	STD [dB]	Mean Error  [dB]
200	0.10	0.02	0.10	0.10	0.10	0.50	0.09	1.01
300	0.08	0.01	0.08	0.10	0.08	0.50	0.07	1.01
400	0.06	0.01	0.06	0.10	0.06	0.50	0.05	1.01
500	0.06	0.01	0.06	0.10	0.06	0.50	0.05	1.01

#### M.3.2.1.4 Power class 4 devices

TBD

### M.4 TRP Measurement Grid

Editor's note: Other implementations are not precluded as far as the respective analysis are presented and included in this TS

### M.4.1 UE Power Classes

#### M.4.1.1 Power class 1 devices

In order to make a reasonable trade-off between measurement uncertainties, at least the following number of points shall be included in the measurement grid for TRP measurements PC1 UEs based on the assumption that the standard deviation does not exceed 0.25dB. If the re-positioning concept is not applied to TRP test cases:

- 480 measurement grid points for constant density grid Charged Particle implementation, with standard deviation of 0.23 dB
- 25 latitudes and 48 longitudes (1106 unique grid points) for constant step size grid sin (theta) weights integration approach, with standard deviation of 0.07dB with the allowance to skip and interpolate measurements at the pole at  $\theta$ =180°, see Annex M.4.4
- 21 latitudes and 40 longitudes (762 unique grid points) for constant step size grid Clenshaw Curtis weights integration approach, with standard deviation of 0.24 dB with the allowance to skip and interpolate measurements at the pole at  $\theta$ =180°, see Annex M.4.4

If the re-positioning concept is applied to TRP test cases:

- 500 measurement grid points for constant density grid Charged Particle implementation, with standard deviation of 0.24 dB with the allowance to skip and interpolate measurements beyond 165° in θ, see Annex M.4.4
- 25 latitudes and 48 longitudes (1106 unique grid points) for constant step size grid sin (theta) weights integration approach, with standard deviation of 0.14dB with the allowance to skip and interpolate measurements beyond 165° in  $\theta$ , see Annex M.4.4
- 21 latitudes and 40 longitudes (762 unique grid points) for constant step size grid Clenshaw Curtis weights integration approach, with standard deviation of 0.25 dB with the allowance to skip and interpolate measurements beyond 162° in θ, see Annex M.4.4

25 latitudes and 48 longitudes (1106 unique grid points) for constant step size grid – Clenshaw Curtis weights integration approach, with standard deviation of 0.15 dB with the allowance to skip and interpolate measurements beyond 150° in θ, see Annex M.4.4

#### M.4.1.2 Power class 2 devices

TBD

#### M.4.1.3 Power class 3 devices

In order to make a reasonable trade-off between measurement uncertainties, at least the following number of points should be included in the measurement grid for TRP measurements for non-sparse antenna arrays case. If the repositioning concept is not applied to TRP test cases:

- 135 measurement grid points for constant density grid Charged Particle implementation, with standard deviation of 0.23 dB<sup>-</sup>
- 12 latitudes and 19 longitudes for constant step size grid sin (theta) weights integration approach, with standard deviation of 0.25dB with the allowance to skip and interpolate measurements at the pole at  $\theta$ =180°.
- 12 latitudes and 19 longitudes for constant step size grid Clenshaw Curtis weights integration approach, with standard deviation of 0.20 dB with the allowance to skip and interpolate measurements at the pole at  $\theta$ =180°.

If the re-positioning concept is applied to TRP test cases:

- 135 measurement grid points for constant density grid Charged Particle implementation, with standard deviation of 0.23 dB with the allowance to skip and interpolate measurements beyond 165° in θ, see Annex M.4.4
- 150 measurement grid points for constant density grid Charged Particle implementation, with standard deviation of 0.25 dB with the allowance to skip and interpolate measurements beyond 150° in θ, see Annex M.4.4
- 12 latitudes and 19 longitudes for constant step size grid sin (theta) weights integration approach, with standard deviation of 0.25dB with the allowance to skip and interpolate measurements the at pole at  $\theta$ =180°, see Annex M.4.4
- 12 latitudes and 19 longitudes for constant step size grid Clenshaw Curtis weights integration approach, with standard deviation of 0.20 dB with the allowance to skip and interpolate measurements the at pole at  $\theta$ =180°, see Annex M.4.4
- 13 latitudes and 24 longitudes for constant step size grid sin (theta) weights integration approach, with standard deviation of 0.21dB with the allowance to skip and interpolate measurements beyond 150° in  $\theta$ , see Annex M.4.4
- 13 latitudes and 24 longitudes for constant step size grid Clenshaw Curtis weights integration approach, with standard deviation of 0.15 dB with the allowance to skip and interpolate measurements beyond 150° in  $\theta$ , see Annex M.4.4.

Choice of grid(s) among above 3 types of grids is up to test system implementation.

#### M.4.1.4 Power class 1 devices

TBD

### M.4.2 TRP Integration for Constant Step Size Grid Type

Different approaches to perform the TRP integration from the respective EIRP measurements are outlined in the next sub clauses for the constant step size grid type.

#### M.4.2.1 TRP Integration using Weights

In many engineering disciplines, the integral of a function needs to be solved using numerical integration techniques, commonly referred to as "quadrature". Here, the approximation of the integral of a function is usually stated as a

weighted sum of function values at specified points within the domain of integration. The derivation from the closed surface TRP integral

$$TRP = \oint_{S} \frac{EIRP(\theta, \phi)}{4\pi} \cdot \sin\theta \cdot d\theta \, d\phi$$

to the classical discretized summation equation used for OTA

$$TRP \approx \frac{\pi}{2 NM} \sum_{i=1}^{N-1} \sum_{j=0}^{M-1} \left[ EIRP_{\theta}(\theta_i, \phi_j) + EIRP_{\phi}(\theta_i, \phi_j) \right] \sin(\theta_i)$$

The weights for this integral are based on the  $\sin\theta \cdot \Delta\theta$  weights. More accurate implementations are based on the Clenshaw-Curtis quadrature integral approximation based on an expansion of the integrand in terms of Chebyshev polynomials. This implementation does not ignore the measurement points at the poles ( $\theta=0^{\circ}$  and  $180^{\circ}$ ) where  $\sin\theta=0$ . The discretized TRP can be expressed as

$$TRP \approx \frac{1}{2M} \sum_{i=0}^{N} \sum_{j=0}^{M-1} \left[ EIRP_{\theta}(\theta_{i}, \phi_{j}) + EIRP_{\phi}(\theta_{i}, \phi_{j}) \right] W(\theta_{i})$$

which the  $\sin\theta \cdot \Delta\theta$  weights replaced by a weight function  $W(\theta)$  and extends the sum over I to include the poles. There is no simple closed-form expression for the Clenshaw-Curtis weights; however, a numerical straightforward approach is available, i.e.,

$$W(\theta_i) = \frac{c_i}{N} \left[ 1 - \sum_{j=1}^{\operatorname{int}\left(\frac{N}{2}\right)} \frac{b_j}{4j^2 - 1} \cos(2j\theta_i) \right]$$

with

and

$$c_{i} = \begin{cases} 1, & i = 0 \text{ or } N\\ 2, & otherwise \end{cases}$$

2j = Notherwise

 $b_j = \begin{cases} 1, \\ 2, \end{cases}$ 

The Clenshaw-Curtis weights are compared to the classical  $\sin \theta \cdot \Delta \theta$  weights in Tables M.4.2.1-1 and M.4.2.1-2 for two different numbers of latitudes. The TRP measurement grid consists of N+1 latitudes and M longitudes with

$$\theta_i = i\Delta\theta$$
 where  $\Delta\theta = \frac{\pi}{N}$ 

and

$$\phi_j = j\Delta\phi$$
 where  $\Delta\phi = \frac{2\pi}{M}$ 

Classica	Classical sin $\theta \Delta \theta$		w-Curtis
θ [deg]	Weights	θ [deg]	Weights
0	0	0	0.008
16.4	0.08	16.4	0.079
32.7	0.154	32.7	0.155
49.1	0.216	49.1	0.216
65.5	0.26	65.5	0.26
81.8	0.283	81.8	0.283
98.2	0.283	98.2	0.283
114.6	0.26	114.6	0.26
130.9	0.216	130.9	0.216
147.3	0.154	147.3	0.155
163.6	0.08	163.6	0.079
180	0	180	0.008

## Table M.4.2.1-1: Samples and weights for the classical sin $\theta \cdot \Delta \theta$ weighting and Clenshaw-Curtis quadratures with 12 latitudes ( $\Delta \theta$ =16.4°)

Table M.4.2.1-2: Samples and weights for the classical sin  $\theta \cdot \Delta \theta$  weighting and Clenshaw-Curtis quadratures with 13 latitudes ( $\Delta \theta$ =15°)

Classica	al sinθ·∆θ	Clensha	w-Curtis
θ [deg]	Weights	θ [deg]	Weights
0	0	0	0.007
15	0.0678	15	0.0661
30	0.1309	30	0.1315
45	0.1851	45	0.1848
60	0.2267	60	0.227
75	0.2529	75	0.2527
90	0.2618	90	0.262
105	0.2529	105	0.2527
120	0.2267	120	0.227
135	0.1851	135	0.1848
150	0.1309	150	0.1315
165	0.0678	165	0.0661
180	0	180	0.007

### M.4.3 TRP Integration for Constant Density Grid Types

For constant density grid types, the TRP integration should ideally take into account the area of the Voronoi region surrounding each grid point. Assuming an ideal constant density configuration of the grid points, the TRP can be approximated using

$$TRP \approx \frac{1}{N} \sum_{i=0}^{N-1} \left[ EIRP_{\theta}(\theta_i, \phi_i) + EIRP_{\phi}(\theta_i, \phi_i) \right]$$

where N is the number of grid points of the constant density grid type.

### M.4.4 Interpolation at or near the Pole

As illustrated in Figure M.4.4-1, for systems that either do not allow measurements at the pole ( $\theta$ =180°), e.g., using distributed-axes positioners, or systems that have the positioners/support structures block the radiation towards the pole ( $\theta$ =180°), e.g., combined-axes positioners, measurements beyond 150° in  $\theta$  can be skipped and interpolated instead for measurement grids defined in Annex M.4.1.

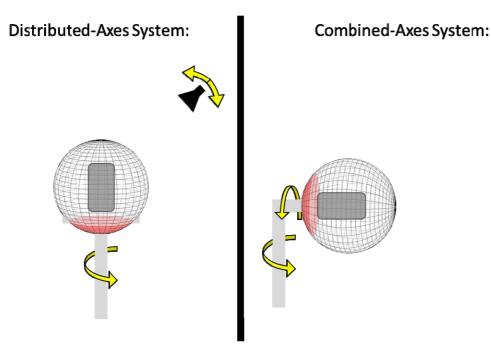


Figure M.4.4-1: Illustration of areas around the pole that either cannot be reached by the measurement antenna or are blocked by the positioner

### M.4.5 TRP Grids for Spurious Emissions

The worst antenna array assumptions for the MU simulations are outlined in Tables M.4.5-1 and M.4.5-2.

Antenna element horizontal radiation pattern	$A_{E,H}(\varphi) = -\min\left[12\left(\frac{\varphi}{\varphi_{3dB}}\right)^2, A_m\right] dB$ , Am =30 dB
Horizontal half-power beam width of single element	260°
Antenna element vertical radiation pattern	$A_{E,V}(\theta) = -\min\left[12\left(\frac{\theta - 90}{\theta_{3dB}}\right)^2, SLA_v\right], SLA_v = 30 \text{ dB}$
Vertical half-power beam width of single array element	130°
Array element radiation pattern	$A_{E}(\varphi,\theta) = G_{E,\max} - \min\left\{-\left[A_{E,H}(\varphi) + A_{E,V}(\theta)\right], A_{m}\right\}$
Element gain without antenna losses	G <sub>E,max</sub> = 1.5 dBi

	$\begin{aligned} A_{A,Beami}(\theta,\varphi) &= A_E(\theta,\varphi) + 10\log_{10} \left( \left  \sum_{m=1}^{N_H} \sum_{n=1}^{N_V} w_{i,n,m} \cdot v_{n,m} \right ^2 \right) \end{aligned}$ the super position vector is given by: $v_{n,m} &= \exp\left( i \cdot 2\pi \left( (n-1) \cdot \frac{d_V}{\lambda} \cdot \cos(\theta) + (m-1) \cdot \frac{d_H}{\lambda} \cdot \sin(\theta) \cdot \sin(\varphi) \right) \right), \end{aligned}$ $n = 1, 2, \dots, N_V; m = 1, 2, \dots, N_H; $ the weighting is given by: $w_{i,n,m} &= \frac{1}{\sqrt{N_H N_V}} \exp\left( i \cdot 2\pi \left( (n-1) \cdot \frac{d_V}{\lambda} \cdot \sin(\theta_{i,etilt}) - (m-1) \cdot \frac{d_H}{\lambda} \cdot \cos(\theta_{i,etilt}) \cdot \sin(\varphi_{i,escan}) \right) \right) \end{aligned}$
Antenna array configuration (Row×Column)	8 x 2
Horizontal radiating element spacing, $d_h/\lambda$	1
Vertical radiating element spacing, d <sub>v</sub> /λ	1

The TRP measurement grid selection for spurious emissions is up to test system implementation but shall meet the criteria shown in Table M.4.5-3.

Table M.4.5-3: TRP measurement grid requirement for spurious emission measurements

Level of Grid	Grid Type	Standard Deviation of MU Element 'Influence of TRP Measurement'	Systematic error due to TRP calculation/quadrature	Number of unique grid points
Cooroo	Constant Density	N/A	N/A	35
Coarse	Constant- Step Size	N/A	N/A	62 (Δθ=Δφ=30°)
Fine	Constant Density	0.32dB	0dB	135
Fine	Constant- Step Size	0.31dB	0dB	266 (Δθ=Δφ=15°)

For spurious emissions, TRP measurements with measurement antennas displaced up to 10° from the focal point (based on electrical switching) in an IFF (based on CATR) test system, alternate TRP approaches for constant-step size grids are allowed for the coarse and fine grids:

interpolation to the non-offset system coordinate system that allows the use of Clenshaw-Curtis or classical  $sin(\theta)$  quadratures

use of the advanced Jacobian matrix quadrature approach that uses triangulations of the sphere

## Annex N (normative): UE coordinate system

### N.1 Reference coordinate system

This annex defines the measurement coordinate system for the NR UE. The reference coordinate system as defined in IEEE Std 149 [27] is provided in Figure N.1-1 below while Figure N.1.-2 shows an example DUT in the default alignment, i.e., the DUT and the reference coordinate systems are aligned with  $\alpha = 0^{\circ}$  and  $\beta = 0^{\circ}$  and  $\gamma = 0^{\circ}$  where  $\alpha$ ,  $\beta$ , and  $\gamma$  describe the relative angles between the two coordinate systems.

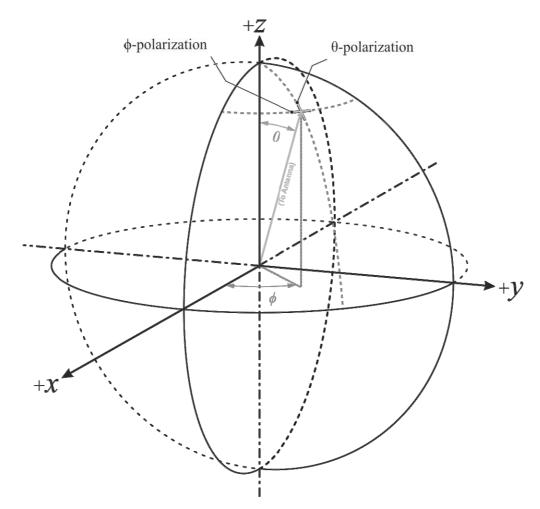
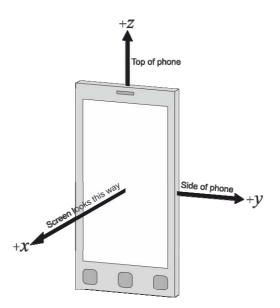


Figure N.1-1: Reference coordinate system



#### Figure N.1-2: Example of DUT default alignment to coordinate system

The following aspects are necessary:

- A basic understanding of the top and bottom of the device is needed in order to define unambiguous DUT positioning requirements for the test, e.g., in the drawings used in this annex, the three buttons are on the bottom of the device (front) and the camera is on the top of the device (back).
- An understanding of the origin and alignment the coordinate system inside the test system i.e. the directions in which the x, y, z -axes points inside the test chamber is needed in order to define unambiguous DUT orientation, DUT beam, signal, interference, and measurement angles

## N.2 Test conditions and angle definitions

Tables N.2-1 through N.2-3 below provides the test conditions and angle definitions for three permitted device alignment for smartphones and tablets for the default test condition, DUT orientation 1, and two different options for each permitted device alignment to re-position the device for DUT Orientation 2 as outlined in Figures N.2-1 and N.2-3.

conditionorientationangleangleDiagramFree space DUT Orientation 1 (default) $\alpha = 0^{0}$ ; $\beta = 0^{0}$ ; $\gamma = 0^{0}$ $\theta_{Link}$ ; $\theta_{Link}$ with polarization reference PolLink = $\theta$ or $\phi$ $\theta_{Meas}$ ; $\phi_{Meas}$ with polarization reference PolMeas = $\theta$ or $\phi$ $\theta_{Meas}$ ; $\phi_{Meas}$ with $\rho_{Darization}$ reference PolMeas = $\theta$ or $\phi$ Rotation Matrix $R_{x}(\alpha)$ $\alpha = 0^{0}$ ; $\alpha = 0^{0}$ ; $\beta = 0^{0}$ ; $\gamma = 0^{0}$ $\theta_{Link}$ ; $\theta_{Darization}$ $\theta_{Darization}$ $\phi$ $\theta_{Meas}$ ; $\theta_{Meas}$ $\theta_{Darization}$ $\theta_{Darization}$ $\theta_{Darization}$ $\theta_{Meas}$ ; $\theta_{Darization}$ $\theta_{Darization}$ $\theta_{Darization}$	
Free space DUT Orientation 2 $-$ Option 1 (based on re- positioning approach) $\alpha = 180^{\circ}$ ; $\beta = 0^{\circ}$ ; $\gamma = 0^{\circ}$ $\theta_{Link};\varphi_{Link}withpolarizationreferencePol_Link = \theta or\phi\theta_{Meas};\varphi_{Meas}withpolarizationreferencePol_Meas = \theta or\phi\theta_{Meas};\varphi_{Meas}withpolarizationreferencePol_Meas = \theta or\phi\theta_{Meas};\varphi_{Meas}\varphi_{Meas}\theta_{Meas};\varphi_{Meas}\varphi_{Meas}\theta_{Meas};\varphi_{Meas}\varphi_{Meas}\theta_{Meas};\varphi_{Meas}\varphi_{Meas}\theta_{Meas};\varphi_{Meas}$	,
Free space DUT Orientation 2 - Option 2 (based on re- positioning approach) $\alpha = 0^{\circ}$ ; $\beta = 180^{\circ}$ ; $\gamma = 0^{\circ}$ $\theta_{\text{Link};}$ $\varphi_{\text{Link}}$ with polarization reference Pol_Link = $\theta$ or $\phi$ $\theta_{\text{Meas};}$ $\varphi$ $\theta_{\text{Matrix R_y(a)}$ $\theta_{\text{Matrix R_y(b)}$ $\theta_{M$	
<ul> <li>NOTE 1: A polarization reference, as defined in relation to the reference coordinate system in N.1-1, is maintain each signal angle, link or interferer angle, and measurement angle.</li> <li>NOTE 2: The combination of rotations is captured by matrix M=R<sub>z</sub>(γ)•R<sub>y</sub>(β)•R<sub>x</sub>(α)</li> </ul>	ed for

## Table N.2-1: Test conditions and angle definitions for smartphones and tablets for Alignment Option1

Test condition	DUT orientation	Link angle	Measurement angle	Diagram
Free space DUT Orientation 1 (default)	α = 0o; β = -90o; γ = 0o	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> \$\overline{\Phi_Meas} \$\with \$ polarization \$ reference \$ Pol_Meas = θ or \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$ \$	+Z Rotation Matrix $R_{z}(\gamma)$ Rotation +x Rotation Matrix $R_{y}(\beta)$
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$\begin{array}{l} \alpha = 180^{o};\\ \beta = 90^{o};\\ \gamma = 0^{o} \end{array}$	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix $R_{z}(y)$ +X Rotation Matrix $R_{y}(\beta)$
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	$egin{array}{lll} \alpha &= 0^{o}; \ \beta &= 90^{o}; \ \gamma &= 0^{o} \end{array}$	θ <sub>Link;</sub> Φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix $R_{z}(\gamma)$ Rotation Matrix $R_{y}(\beta)$
each	signal angle, link o	or interferer angle,	ation to the referent and measuremer by matrix M= <i>R</i> <sub>Z</sub> (γ)•	

## Table N.2-2: Test conditions and angle definitions for smartphones and tablets for Alignment Option2

Test condition	DUT orientation	Link angle	Measurement angle	Diagram
Free space DUT Orientation 1 (default)	$\alpha = 90^{\circ};$ $\beta = 0^{\circ};$ $\gamma = 0^{\circ}$	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	$+x$ Rotation Matrix $R_{-}(y)$ Rotation Matrix $R_{x}(\alpha)$ Rotation Matrix $R_{y}(\beta)$
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$ α = -90^{\circ}; $ $ β = 0^{\circ}; $ $ γ = 0^{\circ} $	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix $R_{z}(y)$ Rotation Matrix $R_{x}(\alpha)$ Rotation Matrix $R_{y}(\beta)$
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	$ \begin{aligned} &\alpha = 90^{\circ}; \\ &\beta = 180^{\circ}; \\ &\gamma = 0^{\circ} \end{aligned} $	$\begin{array}{c} \theta_{\text{Link};} \\ \varphi_{\text{Link}} \\ with \\ polarization \\ reference \\ Pol_{\text{Link}} = \theta \text{ or } \\ \varphi \end{array}$	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix $R_{z}(\gamma)$ Rotation Matrix $R_{x}(\alpha)$ +X Rotation Matrix $R_{y}(\beta)$
each s	signal angle, link o	or interferer angle,	ation to the refere and measuremer by matrix $M=R_z(\gamma)^{\circ}$	

## Table N.2-3: Test conditions and angle definitions for smartphones and tablets for Alignment Option 3

Table N.2-4 below provides the test conditions and angle definitions for the permitted device alignment for laptops for the default test condition, DUT orientation 1, and two different options for each permitted device alignment to reposition the device for DUT Orientation 2 as outlined in Figures N.3-1 and N.3-2. The display is open at a lid angle of  $110^{\circ} \pm 5^{\circ}$ , where lid angle is defined as the angle between the front of the display to the levelled base, and the full projected volume is centred inside the test volume.

Test condition	DUT orientation	Link angle	Measurement angle	Diagram
Free space DUT Orientation (default)	$\begin{array}{l} \alpha = 0^{o};\\ \beta = 0^{o};\\ \gamma = 0^{o} \end{array}$	θ <sub>Link;</sub> ¢ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	$\theta_{Meas;}$ $\phi_{Meas}$ with polarization reference Pol <sub>Meas</sub> = $\theta$ or $\phi$	Projectad Height / 2 Postilion Projectad Height / 2 Projectad Height / 2 Projectad Height / 2 Projectad Height / 2 Projectad Height / 2
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$ \begin{aligned} \alpha &= 180^{o}; \\ \beta &= 0^{o}; \\ \gamma &= 0^{o} \end{aligned} $	θ <sub>Link;</sub> ¢ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Rotation Matrix R(r) Matrix R(r) Rotation Matrix R(r) Rotation Matrix R(r)
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	$ α = 0^{\circ}; $ $ β = 180^{\circ}; $ $ γ = 0^{\circ} $	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Rotation Matrix R <sub>1</sub> (r) Matrix R <sub>1</sub> (r) Matrix R <sub>1</sub> (r)
each	signal angle, link o	or interferer angle	ation to the refere , and measuremer by matrix $M=R_z(\gamma)$	

Table N.2-4: Test conditions and angle definitions for laptops

Tables N.2-5 through N.2-7 below provides the test conditions and angle definitions for the three permitted device alignment options for Fixed Wireless Access (FWA) for the default test condition, DUT orientation 1, and two different options for each permitted device alignment to re-position the device for DUT Orientation 2 as outlined in Figures N.3-1 and N.3-2. Due to changes in DUT orientations  $\alpha$ ,  $\beta$ , and  $\gamma$  for the alignment options for FWA proposed in Tables N.2-6 through N.2-7 when compared to those in Tables N.2-2 through N.2-3, new alignment options, i.e., Options 4 and 5, were introduced.

Test condition	DUT	Link	Measurement	Diagram
Free space DUT Orientation 1 (default)	orientation $\alpha = 0^{0};$ $\beta = 0^{0};$ $\gamma = 0^{0}$	elink; φLink; φLink with polarization reference PolLink = θ or φ	e <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	$Rotation$ $Right C + y$ $Rotation$ $Rotation$ $Matrix R_{s}(x)$
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$ α = 180^{\circ}; $ $ β = 0^{\circ}; $ $ γ = 0^{\circ} $	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix $R_{g}(y)$ +X Rotation Matrix $R_{g}(a)$ Rotation Matrix $R_{g}(\beta)$
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	α = 0o; β = 180o; γ = 0o	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	+Z Rotation Matrix R_(y) +X Rotation Matrix R_(a) Rotation Matrix R_(f)
each	signal angle, link o	e, as defined in rel or interferer angle, ttions is captured l	and measuremer	

Table N.2-5: Test conditions and angle definitions for FWA for Alignment Option 1

Test condition	DUT orientation	Link angle	Measurement angle	Diagram							
Free space DUT Orientation 1 (default)	$ α = 90^{\circ}; $ $ β = 0^{\circ}; $ $ γ = 90^{\circ} $	θ <sub>Link</sub> ; φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas</sub> ; φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Matrix $R_{2}(r)$ Rotation Matrix $R_{3}(\alpha)$							
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$ α = -90^{\circ}; $ $ β = 0^{\circ}; $ $ γ = -90^{\circ} $	θ <sub>Link;</sub> φ <sub>Link</sub> with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Matrix $R_{s}(r)$ For and the second seco							
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	$ α = -90^{\circ}; $ $ β = 0^{\circ}; $ $ γ = 90^{\circ} $	θLink; φLink with polarization reference PolLink = θ or φ	θMeas; φMeas with polarization reference PolMeas = θ or φ	Rotation Matrix $R_{2}(r)$ + $x$ Rotation Matrix $R_{2}(\alpha)$							
each	NOTE 1: A polarization reference, as defined in relation to the reference coordinate system in N.1-1, is maintained for each signal angle, link or interferer angle, and measurement angle.         NOTE 2: The combination of rotations is captured by matrix M=R <sub>z</sub> (γ)•R <sub>y</sub> (β)•R <sub>x</sub> (α)										

Table N.2-6: Test conditions and angle definitions for FWA for Alignment Option 4

Test condition	DUT orientation	Link angle	Measurement angle	Diagram
Free space DUT Orientation 1 (default)	$ \begin{aligned} & \alpha = 0^{o}; \\ & \beta = 90^{o}; \\ & \gamma = 0^{o} \end{aligned} $	θ <sub>Link;</sub> ¢Link with polarization reference Pol <sub>Link</sub> = θ or φ	θ <sub>Meas;</sub> ¢ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or ¢	Rotation Matrix $R_{i}(x)$ + $x$ + $x$ Rotation Matrix $R_{i}(x)$ Rotation Matrix $R_{i}(x)$
Free space DUT Orientation 2 – Option 1 (based on re- positioning approach)	$ α = 180^{\circ}; $ $ β = -90^{\circ}; $ $ γ = 0^{\circ} $	$\begin{array}{c} \theta_{\text{Link};} \\ \varphi_{\text{Link}} \\ \text{with} \\ \text{polarization} \\ \text{reference} \\ \text{Pol}_{\text{Link}} = \theta \text{ or} \\ \varphi \end{array}$	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Matrix R <sub>s</sub> (r) Fotation Matrix R <sub>s</sub> (P)
Free space DUT Orientation 2 – Option 2 (based on re- positioning approach)	$ α = 0^{\circ}; $ $ β = -90^{\circ}; $ $ γ = 0^{\circ} $	$\begin{array}{c} \theta_{\text{Link};} \\ \varphi_{\text{Link}} \\ with \\ polarization \\ reference \\ Pol_{\text{Link}} = \theta \text{ or } \\ \varphi \end{array}$	θ <sub>Meas;</sub> φ <sub>Meas</sub> with polarization reference Pol <sub>Meas</sub> = θ or φ	Rotation Matrix R <sub>s</sub> (r) Rotation Matrix R <sub>s</sub> (a) Rotation Matrix R <sub>s</sub> (d)
each s	signal angle, link o	or interferer angle,	ation to the refere and measuremer by matrix $M=R_z(\gamma)$	

Table N.2-7: Test conditions and angle definitions for FWA for Alignment Option 5

For each UE requirement and test case, each of the parameters in Table N.2-1 through N.2-7 need to be recorded, such that DUT positioning, DUT beam direction, and angles of the signal, link/interferer, and measurement are specified in terms of the fixed coordinate system.

Due to the non-commutative nature of rotations, the order of rotations is important and needs to be defined when multiple DUT orientations are tested.

The rotations around the x, y, and z axes can be defined with the following rotation matrices

$$R_{x}(\alpha) = \begin{bmatrix} 1 & 0 & 0 & 0 \\ 0 & \cos \alpha & -\sin \alpha & 0 \\ 0 & \sin \alpha & \cos \alpha & 0 \\ 0 & 0 & 0 & 1 \end{bmatrix}$$
$$R_{y}(\beta) = \begin{bmatrix} \cos \beta & 0 & \sin \beta & 0 \\ 0 & 1 & 0 & 0 \\ -\sin \beta & 0 & \cos \beta & 0 \\ 0 & 0 & 0 & 1 \end{bmatrix}$$

and

$$R_{z}(\gamma) = \begin{bmatrix} \cos \gamma & -\sin \gamma & 0 & 0\\ \sin \gamma & \cos \gamma & 0 & 0\\ 0 & 0 & 1 & 0\\ 0 & 0 & 0 & 1 \end{bmatrix}.$$

with the respective angles of rotation,  $\alpha$ ,  $\beta$ ,  $\gamma$ , and

$$\begin{bmatrix} x'\\y'\\z'\\1 \end{bmatrix} = R \begin{bmatrix} x\\y\\z\\1 \end{bmatrix}$$

Additionally, any translation of the DUT can be defined with the translation matrix

$$T(t_x, t_y, t_z) = \begin{bmatrix} 1 & 0 & 0 & t_x \\ 0 & 1 & 0 & t_y \\ 0 & 0 & 1 & t_z \\ 0 & 0 & 0 & 1 \end{bmatrix}$$

with offsets  $t_x$ ,  $t_y$ ,  $t_z$  in x, y, and z, respectively and with

$$\begin{bmatrix} x' \\ y' \\ z' \\ 1 \end{bmatrix} = T \begin{bmatrix} x \\ y \\ z \\ 1 \end{bmatrix}$$

The combination of rotations and translation is captured by the multiplication of rotation and translation matrices.

For instance, the matrix M

$$M = T(t_x, t_y, t_z) \cdot R_x(\gamma) \cdot R_y(\beta) \cdot R_x(\alpha)$$

describes an initial rotation of the DUT around the x axis with angle  $\alpha$ , a subsequent rotation around the y axis with angle  $\beta$ , and a final rotation around the z axis with angle  $\gamma$ . After those rotations, the DUT is translated by  $t_x$ ,  $t_y$ ,  $t_z$  in x, y, and z, respectively.

## N.3 DUT positioning guidelines

The centre of the reference coordinate system shall be aligned with the geometric centre of the DUT in order to minimize the offset between antenna arrays integrated at any position of the UE and the centre of the quiet zone.

Near-field coupling effects between the antenna and the pedestals/positioners/fixtures generally cause increased signal ripples. Re-positioning the DUT by directing the beam peak away from those areas can reduce the effect of signal ripple on EIRP/EIS measurements. Figure N.3-1 and N.3-2 illustrate how to reposition the DUT in distributed axes and combined axes system, when the beam peak is directed to the DUTs upper hemisphere (DUT orientation 1) or the DUTs lower hemisphere (DUT orientation 2). While these figures are examples of different positioning systems and other implementations are not precluded, the relative orientation of the coordinate system with respect to the antennas/reflectors and the axes of rotation shall apply to any measurement setup.

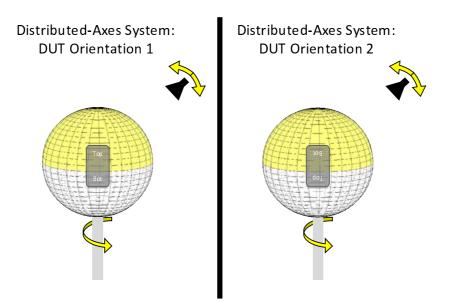


Figure N.3-1: DUT re-positioning for an example of distributed-axes system

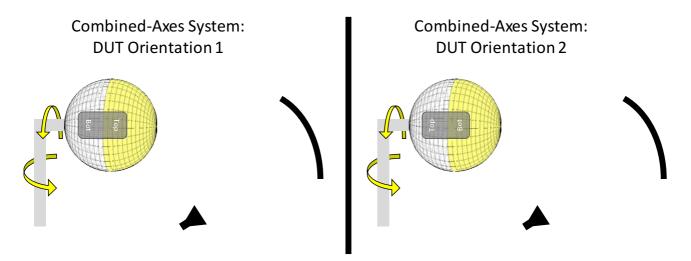


Figure N.3-2: DUT re-positioning for an example of combined-axes system

For EIRP/EIS measurements, re-positioning the DUT makes sure the pedestal is not obstructing the beam path and that the pedestal is not in closer proximity to the measurement antenna/reflector than the DUT. For TRP measurements, re-positioning the DUT makes sure that the beam peak direction is not obstructed by the pedestal and the pedestal is in the

measurement path only when measuring the back-hemisphere. No re-positioning during the TRP measurement is required.

## Annex O: Quality of the quiet zone validation

### O.1 General

This annex describes the procedures for validating the quality of the quiet zone for the permitted far-field methods outlined in Annex B.2.2 (DFF), B.2.3 (simplified DFF), and in B.2.4 (IFF based on CATR) in [10]. Annex O.2 focuses on the procedure for in-band and OOB test cases while Annex O.3 focuses on the procedure for spurious emissions test cases. These procedures are applicable to PC1 and PC3 UEs.

# O.2 Procedure to characterize the quality of the quiet zone for in-band/OOB for the permitted far field methods

This procedure is mandatory before the test system is commissioned for certification tests and characterizes the quiet zone performance of the anechoic chamber, specifically the effect of reflections within the anechoic chamber including any positioners and support structures. Additionally, it includes the effect of offsetting the directive antenna array inside a DUT from the centre of the quiet zone, i.e., the centre of rotation of the DUT and measurement antenna positioning systems as well as the directivity MU, i.e., the variation of antenna gains in the different direct line-of-sight links.

The quiet zone is illustrated in Figure O.2-1 which includes the definitions of centre of quiet zone range, i.e., the geometric centre of the positioning systems, and the range length, i.e., the distance between the centre of the quiet zone and the aperture of the measurement antenna.

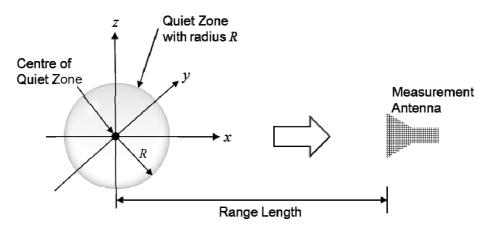


Figure 0.2-1: Quiet Zone Illustration

The outcome of the procedures can be used to predict the

- variation of the TRP measurements, spherical surface integrals of EIRP/EIS, when the DUT is placed anywhere within the quiet zone and with the beam formed in any arbitrary direction inside the chamber
- variation of the EIRP/EIS measurements when the DUT is placed anywhere within the quiet zone and with the beam formed in any arbitrary direction inside the chamber

The reference coordinate system defined in Annex N applies to this procedure.

### O.2.1 Equipment used

The reference antenna under test (AUT) that is placed at various locations within the quiet zone shall be a directive antenna with similar properties of typical antenna arrays integrated in DUTs. The characteristics in terms of Directivity and Half Power Beamwidth (HPBW) of the reference AUT are shown in Figure O.2.1-1, O.2.1-2, and O.2.1-3.

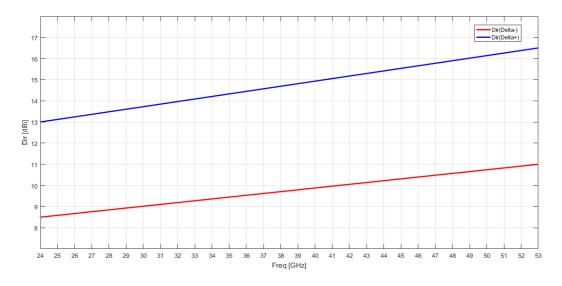


Figure 0.2.1-1: Directivity mask

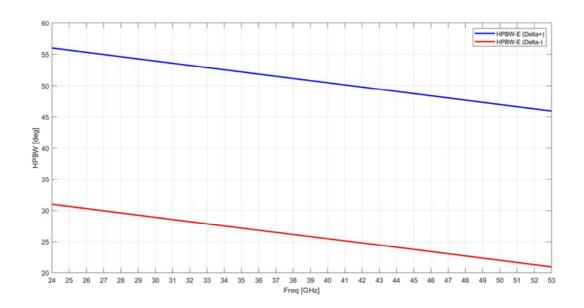


Figure 0.2.1-2: 2xHPBW-E mask

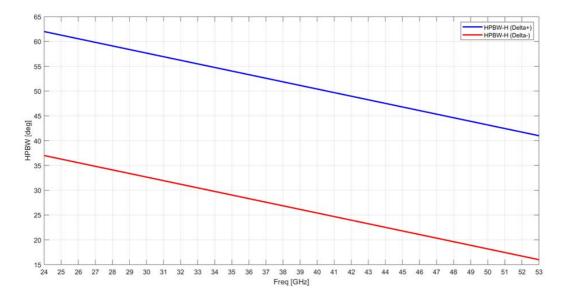


Figure O.2.1-3: 2xHPBW-H mask

AUT shall be symmetric on E and H planes.

The above masks for the reference antenna are met based on antenna vendors' calibration report.

For the measurement, a combination of signal generator and spectrum analyser or a network analyser can be used. The multi-port (with three ports) network analyser is most suitable to reduce test time as both polarizations of the measurement antenna can be measured simultaneously, and multiple frequencies can be measured in a sweep.

#### O.2.2 Test frequencies

The frequencies to be used to characterize the quality of the quiet zone are 23.45 GHz, 32.125 GHz, and 40.8 GHz. The quiet zone validation analysis is performed for each frequency individually.

#### O.2.3 Reference measurements

The quality of the quiet measurements for integrated RF parameters such as TRP shall use 3D pattern measurements of the reference antenna patterns as they most closely resemble the 3D/spherical surface measurements/integrals of EIRP or EIS. Therefore, the quality of the quiet zone measurements for TRP metrics shall be based on efficiency measurements. On the other hand, the quality of the quiet zone measurements for single-directional EIRP and EIS metrics shall be based on gain measurements of the direct line-of-sight link between the reference AUT and the measurement antenna.

The grid types for the TRP measurements shall match those outlined in M.1 and the minimum number of grid points (including quadratures for constant step size grids and implementation of constant density grids) shall meet the 0.25 dB maximum standard uncertainty summarized in M.4.

#### O.2.4 Size of the quiet zone

The size of the quiet zone within which the variations of measurements are evaluated depends on the size of the DUT. For smartphones, the quiet zone shall be considered a sphere with radius of R=10cm. For larger smartphones and tablet type devices, the quiet zone shall be considered a sphere with radius of R=15cm. Alternate quiet zone sizes can be defined for even larger DUTs.

The quality of quiet zone procedure for systems supporting larger quiet zone sizes can be performed for the largest quiet zone radius only and the results can be applied to the smaller quiet zone radius. Performing separate sets of quality of quiet zone measurements for different radii is not precluded.

### O.2.5 Reference AUT positions

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure O.2.5.1-1 and O.2.5.2-1

While position 1, P1, is the centre of the quiet zone, the remaining positions, 2 through 7, are off-centre positions each displaced by the radius of the quiet zone, R. The coordinates of the respective test points are shown in Table O.2.5-1.

Position x y z P1 0 0 0 P2 R 0 0 P3 -R 0 0 Ρ4 0 R 0 P5 0 -R 0 P6 0 0 R P7 0 0 -R

Table 0.2.5-1: Reference AUT Measurement Coordinates

#### O.2.5.1 Distributed-axes system

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure 0.2.5.1-1.

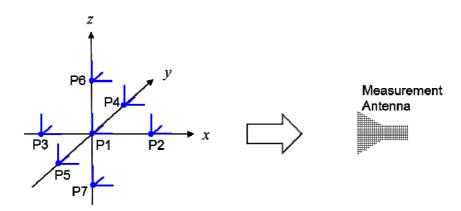


Figure 0.2.5.1-1: Reference AUT Measurement Positions for distributed-axes system

The reference AUT positions inside a typical distributed-axes system are shown in Figure O.2.5.1-2.

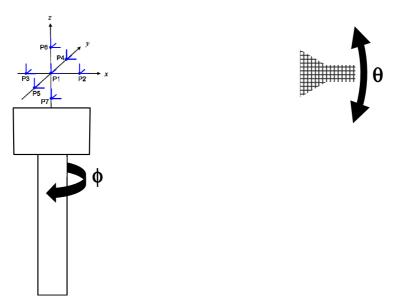


Figure 0.2.5.1-2: Reference AUT Measurement Positions for distributed-axes system

#### O.2.5.2 Combined-axes system

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure O.2.5.2-1.

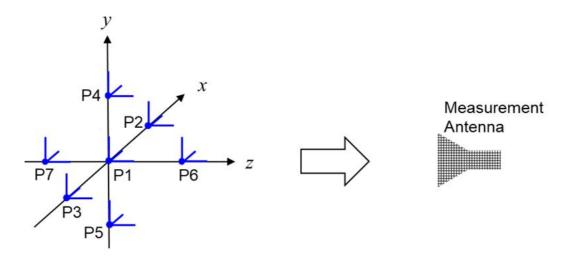


Figure 0.2.5.2-1: Reference AUT Measurement Positions for combined-axes system

The reference AUT positions inside a typical combined-axes system are shown in Figure O.2.5.2-2.

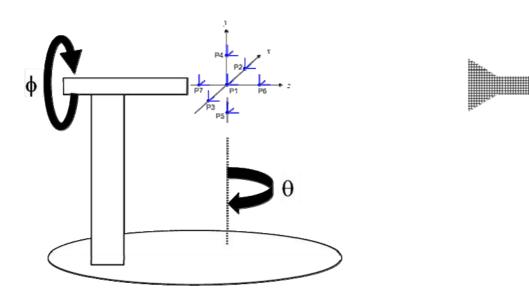


Figure 0.2.5.2-2: Reference AUT Measurement Positions for combined-axes system

#### O.2.6 Reference AUT orientations

As different areas within the chamber could yield variations in the field uniformity inside the quiet zone caused by reflections, it is important to characterize the electromagnetic fields with the reference antennas uniformly illuminating the anechoic chamber.

#### O.2.6.1 Distributed-axes system

In order to keep the quality of the quiet zone characterization manageable in terms of test times, it is suggested to perform the reference measurements for the reference AUT placed at the 7 antenna positions with the antenna rotated around the y axis with 5 different angles  $\beta$ , i.e.,  $\beta = 0^{\circ}$ , 45°, 90°, 135°, and 180°, and rotated around the z axis with 8 different  $\gamma = 0^{\circ}$ , 45°, 90°, 135°, 180°, 225°, 270°, and 315°. A graphical illustration of the some sample reference AUT orientations is shown in Figure O.2.6.1-1 with a reference AUT placed at position 6, P6, for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ ; Figure O.2.6.1-2 illustrates the reference AUT orientations for the reference polarization  $\gamma_{pol} = 90^{\circ}$ .

The matrix operation for the rotations and translation is defined as

$$M = T(t_x, t_y, t_z) \cdot R_z(\gamma) \cdot R_y(\beta) \cdot R_{z, pol}(\gamma_{pol})$$

for the distributed-axes system.

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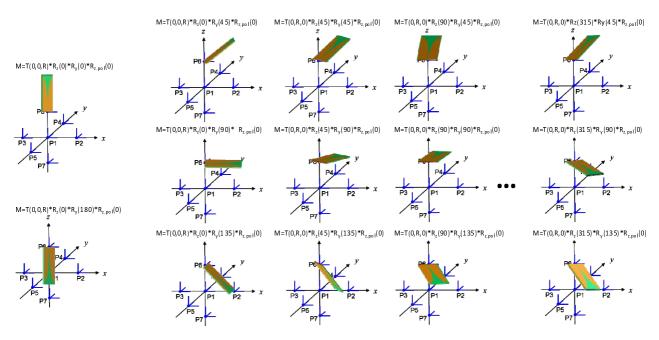


Figure O.2.6.1-1: Sample reference AUT orientations for position 6, P6 for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ 

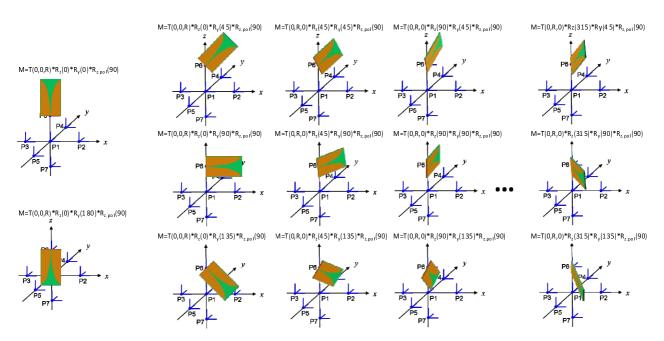


Figure O.2.6.1-2: Sample reference AUT orientations for position 6, P6, for reference antenna polarization  $\gamma_{pol} = 90^{\circ}$ 

When facing the z-axis,  $\beta = 0^{\circ}$  and  $\beta = 180^{\circ}$ , the antenna does not need to be evaluated for the 8 different rotations around the z axis. A single orientation is sufficient since those orientations are unique. Due to the pedestal, distributed-axes systems are not able to measure towards the  $\beta = 180^{\circ}$  direction; for those systems, the reference measurements at this reference AUT orientation can be skipped.

If the device re-positioning approach outlined in Annex N is adopted for the EIRP/EIS/TRP based conformance test cases, the quality of quiet zone analysis is sufficient only for  $\beta = 0^{\circ}$ , 45°, 90°.

The positioner relative coordinates/orientations with respect to the measurement antenna/reflector in the initial position shall remain the same for each reference antenna orientation, e.g., in the sample distributed-axes system shown in

Figure O.2.5.1-2 the reference antenna shall be pointed towards the positioner for  $\beta = 135^{\circ}$  for the initial position of  $(\theta, \phi)$  of (0, 0).

### O.2.6.2 Combined-axes system

In order to keep the quality of the quiet zone characterization manageable in terms of test times, it is suggested to perform the reference measurements for the reference AUT placed at the 7 antenna positions with the antenna rotated around the x axis with 5 different angles  $\alpha$ , i.e.,  $\alpha = -90^{\circ}$ ,  $-45^{\circ}$ ,  $0^{\circ}$ ,  $45^{\circ}$ , and  $90^{\circ}$  and rotated around the y axis with 8 different angles  $\beta = 0^{\circ}$ ,  $45^{\circ}$ ,  $90^{\circ}$ ,  $135^{\circ}$ ,  $180^{\circ}$ ,  $225^{\circ}$ ,  $270^{\circ}$ , and  $315^{\circ}$ . A graphical illustration of some sample reference AUT orientations is shown in Figure O.2.6.2-1 with a reference AUT placed at position 4, P4, for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ ; Figure O.2.6.2-2 illustrates the reference AUT orientations for the reference polarization  $\gamma_{pol} = 90^{\circ}$ .

The matrix operation for the rotations and translation is defined as

$$M = T(t_x, t_y, t_z) \cdot R_y(\beta) \cdot R_x(\alpha) \cdot R_{z, nol}(\gamma_{nol})$$

for the combined-axes system.

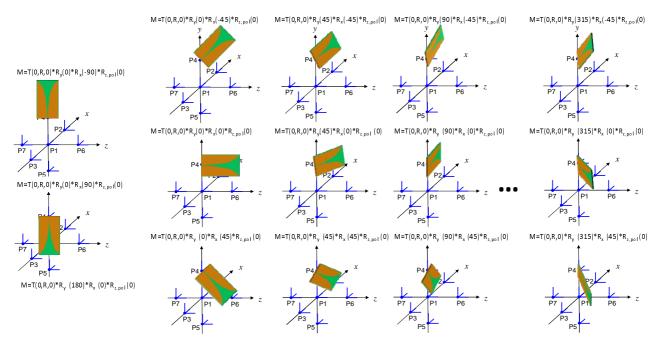


Figure O.2.6.2-1: Sample reference AUT orientations for position 4, P4, for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ 

#### ETSI TS 138 521-2 V16.6.0 (2021-02)

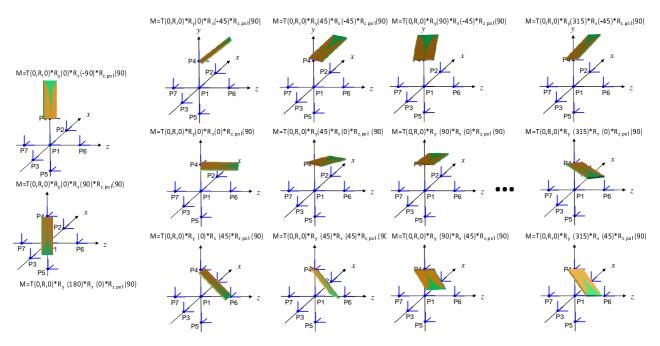


Figure O.2.6.2-2: Sample reference AUT orientations for position 4, P4, for reference antenna polarization  $\gamma_{pol} = 90^{\circ}$ 

When facing the y axis,  $\alpha = 90^{\circ}$  and  $\alpha = -90^{\circ}$ , the antenna does not need to be evaluated for the 8 different rotations around the y axis. A single rotation is sufficient since those orientations are unique. Due to the pedestal of the 2-axis positioner, combined-axes systems are not able to measure towards the  $\beta = 180^{\circ}$  direction; for those systems, the reference measurements at this reference AUT orientation can be skipped.

If the device re-positioning approach outlined in Annex N is adopted for all EIRP/EIS/TRP based conformance test cases, the quality of quiet zone analysis is sufficient only for  $\beta = 0^{\circ}$ , 45°, 90°, 270°, and 315°.

The positioner relative coordinates/orientations with respect to the measurement antenna/reflector shall remain the same for each reference antenna orientation, e.g., in the sample combined-axes system shown in O.2.5.2-2 the reference antenna shall be pointed towards the positioner for  $\beta = 135^{\circ}$  and  $225^{\circ}$  for the initial position of  $(\theta, \phi)$  of (0, 0).

#### O.2.7 Quality of quiet zone measurement uncertainty calculations for TRP

The combined MU element related to the quality of the quiet zone for TRP and offset between UE antenna array and centre of quiet zone is the standard deviation of the various efficiency measurement results that are based on the 7 different reference AUT positions, the respective reference AUT orientations, and the two reference AUT polarization orientations.

#### O.2.8 Quality of quiet zone measurement uncertainty for EIRP/EIS

The MU for the quality of the quiet zone for EIRP/EIS includes the additional MU element of the directivity of the DUT and measurement antennas as shown in Figure O.2.9-1. The EIRP/EIS measurements are taking the peak gains of the respective antennas into account with the reference AUT placed in the centre of the quiet zone. Once the antenna is displaced in directions other than the measurement antenna, the direct line-of-sight link is taking reduced antenna gains into account. The type of reference AUT should therefore have similar pattern properties as typical UE antennas. For systems with very large range lengths, the directivity MU will be insignificant.

The combined MU element related to the quality of the quiet zone for EIRP/EIS, offset between UE antenna array and centre of quiet zone, and directivity is the standard deviation of the single-point gain measurement results that are based on the 7 different reference AUT positions, the respective reference AUT orientations, and the two reference AUT polarization orientations.

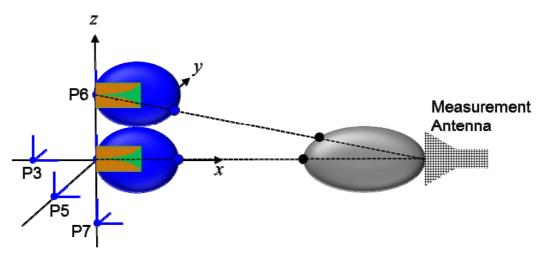


Figure 0.2.9-1: Illustration of the Directivity MU Element

# O.3 Procedure to characterize the spurious emissions quality of the quiet zone for the permitted far field methods

This procedure is mandatory before the spurious emissions test system is commissioned for certification tests and characterizes the quiet zone performance of the anechoic chamber, specifically the effect of reflections within the anechoic chamber including any positioners and support structures. Additionally, it includes the effect of offsetting the directive antenna array inside a DUT from the centre of the quiet zone, i.e., the centre of rotation of the DUT and measurement antenna positioning systems.

The quiet zone is illustrated in Figure O.2-1 which includes the definitions of centre of quiet zone range, i.e., the geometric centre of the positioning systems, and the range length, i.e., the distance between the centre of the quiet zone and the aperture of the measurement antenna.

The outcome of the procedures can be used to predict the variation of the TRP measurements, spherical surface integrals of EIRP, when the DUT is placed anywhere within the quiet zone and with the beam formed in any arbitrary direction inside the chamber

The reference coordinate system defined in Annex N applies to this procedure.

#### O.3.1 Equipment used

The reference antenna under test (AUT) that is placed at various locations within the quiet zone shall be a directive antenna with a half-power beam width (HPBW) of  $\geq 20^{\circ}$  in E-Plane and H-Plane. The HPBWs met based on antenna vendors' calibration report or datasheet.

For the measurement, a combination of signal generator and spectrum analyser or a network analyser can be used. The multi-port (with three ports) network analyser is most suitable to reduce test time as both polarizations of the measurement antenna can be measured simultaneously, and multiple frequencies can be measured in a sweep.

#### O.3.2 Test frequencies

Editor Note: Another test frequency of [TBD] GHz will be added as soon as FR2 bands >40GHz are introduced.

The frequencies to characterize the quality of the quiet zone shall be 6, 12.75, 23.45, 40.8, 66, and 80GHz. The quiet zone validation analysis is performed for each frequency individually.

The measurements from the 23.45 and 40.8GHz in-band QoQZ validation can be re-used provided that the reference antenna position and orientation as well as the measurement frequency and measurement antenna are identical in both cases.

### O.3.3 Reference measurements

The spurious emissions quality of the quiet zone measurements shall use 3D pattern measurements of the reference antenna patterns as they most closely resemble the 3D/spherical surface measurements/integrals of EIRP. Therefore, the quality of the quiet zone measurements for TRP metrics shall be based on efficiency measurements.

The grid types for the TRP measurements shall meet the 0.25 dB maximum standard uncertainty. The min number of grid points for the two grid types are:

- 192 grid points for the constant step-size measurement grids
- 100 grid points for the constant density measurement grids (charged particle implementation)

### O.3.4 Size of the quiet zone

The size of the quiet zone within which the variations of measurements are evaluated depends on the size of the DUT. For smartphones, the quiet zone shall be considered a sphere with radius of R=10cm. For larger smartphones and tablet type devices, the quiet zone shall be considered a sphere with radius of R=15cm. Alternate quiet zone sizes can be defined for even larger DUTs.

The quality of quiet zone procedure for systems supporting larger quiet zone sizes can be performed for the largest quiet zone radius only and the results can be applied to the smaller quiet zone radius. Performing separate sets of quality of quiet zone measurements for different radii is not precluded.

### O.3.5 Reference AUT positions

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure O.2.5.1-1 and O.2.5.2-1

While position 1, P1, is the centre of the quiet zone, the remaining positions, 2 through 7, are off-centre positions each displaced by the radius of the quiet zone, R. The coordinates of the respective test points are shown in Table O.2.5-1.

#### O.3.5.1 Distributed-axes system

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure O.2.5.1-1 for distributed-axes systems.

The reference AUT positions inside a typical distributed-axes system are shown in Figure O.2.5.1-2.

### O.3.5.2 Combined-axes system

The reference AUT shall be positioned in a total of 7 different reference positions, shown in Figure O.2.5.2-1 for combined-axes systems.

The reference AUT positions inside a typical combined-axes system are shown in Figure O.2.5.2-2.

### O.3.6 Reference AUT orientations

As different areas within the chamber could yield variations in the field uniformity inside the quiet zone caused by reflections, it is important to characterize the electromagnetic fields with the reference antennas uniformly illuminating the anechoic chamber. However, in order to keep the spurious emissions quality of the quiet zone characterization manageable in terms of test time, the number of orientations for the spurious emissions quality of quiet zone validation is limited when compared to the number of orientations for the in-band quality of quiet zone validation.

#### O.3.6.1 Distributed-axes system

The reference measurements for the reference AUT placed at the 7 antenna positions shall be rotated around the *y* axis with 2 different angles  $\beta$ , i.e.,  $\beta = 0^{\circ}$  and 180° and fixed  $\gamma = 0^{\circ}$ . A graphical illustration of the reference AUT orientations is shown in Figure O.3.6.1-1 with a reference AUT placed at position 6, P6, for reference antenna

polarization  $\gamma_{pol} = 0^{\circ}$ ; Figure O.3.6.1-2 illustrates the reference AUT orientations for the reference polarization  $\gamma_{pol} = 90^{\circ}$ .

The matrix operation for the rotations and translation is defined as

$$M = T(t_x, t_y, t_z) \cdot R_z(\gamma) \cdot R_y(\beta) \cdot R_{z, pol}(\gamma_{pol})$$

for the distributed-axes system. The matrices are defined in Annex J.2 of TS 38.101-2.

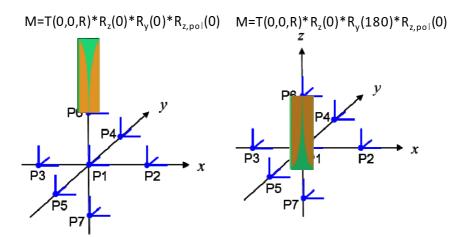


Figure O.3.6.1-1: Reference AUT orientations for position 6, P6 for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ 

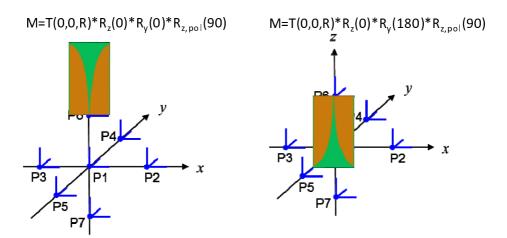


Figure 0.3.6.1-2: Reference AUT orientations for position 6, P6, for reference antenna polarization  $\gamma_{pol} = 90^{\circ}$ 

If the device re-positioning approach is adopted for the spurious emissions test cases, i.e., two hemispheres are measured separately which involves the DUT, while connected to the gNB emulator, to be rotated by 180° around its axis halfway through the test, the quality of quiet zone analysis is sufficient only for  $\beta = 0^\circ$ .

The positioner relative coordinates/orientations with respect to the measurement antenna/reflector in the initial position shall remain the same for each reference antenna orientation, e.g., in the sample distributed-axes system shown in Figure O.2.5.1-2 the reference antenna shall be pointed at the positioner for  $\beta = 180^{\circ}$  for the initial position of  $(\theta, \phi)$  of (0,0).

#### O.3.6.2 Combined-axes system

The reference measurements for the reference AUT placed at the 7 antenna positions shall be rotated around the *x* axis with 2 different angles  $\beta$ , i.e.,  $\beta = 0^{\circ}$  and 180° and fixed  $\alpha = 0^{\circ}$ . A graphical illustration of the sample reference AUT orientations is shown in Figure O.3.6.2-1 with a reference AUT placed at position 4, P4, for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ ; Figure O.3.6.2-2 illustrates the reference AUT orientations for the reference polarization  $\gamma_{pol} = 90^{\circ}$ .

The matrix operation for the rotations and translation is defined as

$$M = T(t_x, t_y, t_z) \cdot R_y(\beta) \cdot R_x(\alpha) \cdot R_{z, pol}(\gamma_{pol})$$

for the combined-axes system. The matrices are defined in Annex J.2 of TS 38.101-2.

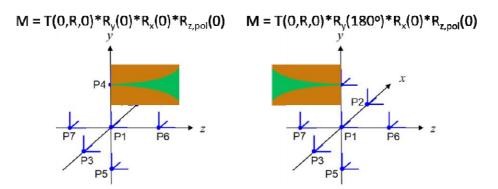


Figure O.3.6.2-1: Reference AUT orientations for position 4, P4, for reference antenna polarization  $\gamma_{pol} = 0^{\circ}$ .

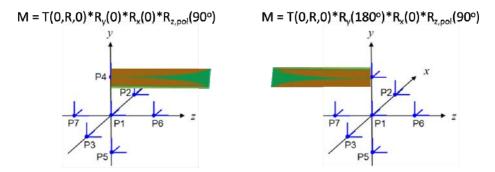


Figure O.3.6.2-2: Reference AUT orientations for position 4, P4, for reference antenna polarization  $\gamma_{pol} = 90^{\circ}$ 

If the device re-positioning approach is adopted for the spurious emissions test cases, i.e., two hemispheres are measured separately which involves the DUT, while connected to the gNB emulator, to be rotated by 180° around its axis halfway through the test, the quality of quiet zone analysis is sufficient only for  $\beta = 0^\circ$ .

The positioner relative coordinates/orientations with respect to the measurement antenna/reflector shall remain the same for each reference antenna orientation, e.g., in the sample combined-axes system shown in O.2.5.2-2 the reference antenna shall be pointed at the positioner for  $\beta = 180^{\circ}$  for the initial position of  $(\theta, \phi)$  of (0, 0).

#### 0.3.7 Quality of quiet zone measurement uncertainty calculations for TRP

The combined MU element related to the spurious emissions quality of the quiet zone for TRP and offset between UE antenna array and centre of quiet zone is the standard deviation of the various efficiency measurement results that are

based on the 7 different reference AUT positions, the respective reference AUT orientations, and the two reference AUT polarization orientations.

## Annex P (normative): Modified MPR behaviour

### P.1 Indication of modified MPR behaviour

This annex contains the definitions of the bits in the field *modifiedMPR-Behavior* indicated per supported NR band in the IE *RF-Parameters* [19] by a UE supporting an MPR or A-MPR modified in a given version of this specification. A modified MPR or A-MPR behaviour can apply to a supported NR band in stand-alone operation (including CA and NN-DC operation) or in non-standalone operation with the said NR band as part of an EN-DC or NE-DC band combination.

NOTE 1: In the present release, the *modifiedMPR-Behavior* is indicated [19] by an 8-bit bitmap per supported NR band.

NR Band	Index of field	Definition	Notes
	(bit number)	(description of the supported functionality if	
		indicator set to one)	
n257	0 (leftmost bit)	- FR2 power class 3 MPR as defined in clause	- This bit may be set to 1 by
112.57		6.2.2.3 of 38.101-2 v16.2.0	a UE supporting n257
n258	0 (leftmost bit)	- FR2 power class 3 MPR as defined in clause	- This bit may be set to 1 by
11200		6.2.2.3 of 38.101-2 v16.2.0	a UE supporting n258
n258	1	- AMPR for NS_201 as defined in clause 6.2.3.2	- This bit may be set to 1 by
112.50	ļ	of 38.101-2 v15.7.0	a UE supporting n258
n260	0 (leftmost bit)	- FR2 power class 3 MPR as defined in clause	- This bit may be set to 1 by
11200		6.2.2.3 of 38.101-2 v16.2.0	a UE supporting n260
n261	0 (loftmost bit)	- FR2 power class 3 MPR as defined in clause	- This bit may be set to 1 by
11201	0 (leftmost bit)	6.2.2.3 of 38.101-2 v16.2.0	a UE supporting n261

#### Table P.1-1: Definitions of the bits in the field modifiedMPRbehavior

## Annex Q (informative): Change history

	Change history						
Date	Meeting	TDoc	CR	R ev	Cat	Subject/Comment	New version
2017-08	RAN5 #76	R5-174709	-	-	-	Draft skeleton	0.0.1
2018-01	RAN5#1- 5G-NR Adhoc	R5-180002	-	-	-	Add references	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180103	-	-	-	Add definitions, symbols and abbreviations	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180104	-	-	-	Introduction of Operating bands and Channel arrangement	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180094	-	-	-	Introduction of new test case 6.3.2 Transmit OFF power	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180095	-	-	-	TP to add skeleton of 6.5.1 Occupied bandwidth to 38.521-2	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180096	-	-	-	TP to add skeleton of 6.5.2.1 SEM to 38.521-2	0.1.0
2018-01	RAN5#1- 5G-NR Adhoc	R5-180097	-	-	-	TP to add skeleton of 6.5.2.3 ACLR to 38.521-2	0.1.0
2018-03	RAN5 #78	R5-181508	-	-	-	Updated 38.521-2 to extend Annex with additional testing information	0.2.0
2018-03 2018-03	RAN5 #78 RAN5 #78	R5-181680 R5-181681	-	-	-	TP to skeleton of 7.6.1 Inband blocking to 38.521-2 5G-NR: Text Proposal to add spurious emissions test case to 38.521-2	0.2.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-181978	-	-	-	Update TS 38.521-2 further to align with the latest TS 38.101-2 spec structure.	0.3.1
2018-04	RAN5#2- 5G-NR Adhoc	R5-182027	-	-	-	5G-NR Text Proposal to update spurious emissions test case to 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182041	-	-	-	5G-NR Text Proposal to add REFSENS test case to 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182009	-	-	-	General section updated to 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182048	-	-	-	Addition of FR2 test case 6.3.1 Minimum Output Power	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182049	-	-	-	Addition of FR2 test case 6.3.3.2 General ON/OFF time mask	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-181839	-	-	-	Definitions and abbreviations updated to 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-181840	-	-	-	Operating bands and Channel arrangement updated to 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182008	-	-	-	Introduction of new test case 7.4 Maximum input level	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182010	-	-	-	Common uplink configuration table for Tx test cases for TS 38.521-2 non-CA	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182011	-	-	-	TP for 6.5.1 Occupied Bandwidth in TS 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR Adhoc	R5-182029	-	-	-	TP for 6.5.2.1 Spectrum Emission Mask in TS 38.521-2	0.4.0
2018-04	RAN5#2- 5G-NR	R5-182031	-	-	-	TP for 6.5.2.3 Adjacent Channel Leakage Ratio in TS 38.521-2	0.4.0

	Adhoc						
2018-04	RAN5#2-	R5-182043	-	-	-	TP for 7.6.2 InBand Blocking in TS 38.521-2	0.4.0
	5G-NR						
	Adhoc	_					
2018-04	RAN5#2-	R5-182046	-	-	-	TP for 7.5 Adjacent channel selectivity in TS 38.521-2	0.4.0
	5G-NR Adhoc						
2018-04	RAN5#2-	R5-181844	1_	-	-	Add Annex G (normative): Measurement uncertainties and Test	0.4.0
2010 04	5G-NR	110 101044				Tolerances	0.4.0
	Adhoc						
2018-04	RAN5#2-	R5-181844	-	-	-	Add clause 4.4 Test point analysis	0.4.0
	5G-NR						
	Adhoc						
	RAN5 #79	R5-183908	-	-	-	Introduction of New FR2 test case 6.3.3.4 PRACH time mask	0.5.0
	RAN5 #79	R5-182769	-	-	-	General section updated to 38.521-2	0.5.0
	RAN5 #79	R5-183914	-	-	-	TP for FR2 spurious test procedure (38.521-2)	0.5.0
	RAN5 #79	R5-183925	-	-	-	Update of Refsens test procedure for FR2	0.5.0
	RAN5 #79	R5-182883	-	-	-	Definitions, symbols and abbreviations updated to 38.521-2	0.5.0
	RAN5 #79	R5-182884	-	-	-	Operating bands and Channel arrangement updated to 38.521-2	0.5.0
2018-05	RAN5 #79	R5-182890	-	-	-	Update minimum conformance requirements and test requirement	0.5.0
						for 6.3.2 Transmit OFF power	
	RAN5 #79	R5-183926	-	-	-	Annex for test case applicability per permitted test method	0.5.0
	RAN5 #79	R5-183712	-	-	-	Corrections annexes for EIRP and TRP metric definition	0.5.0
	RAN5 #79	R5-183927	-	-	-	Clean up TBD from Occupied Bandwidth, SEM and ACLR test cases	0.5.0
	RAN5 #79	R5-183928	-	-	-	Clean up TBD from ACS and Inband Blocking test cases	0.5.0
2018-05	RAN5 #79	R5-183948	-	-	-	Statistical Testing Annex for 38.521-2	0.5.0
2018-08	RAN5 #80	R5-185348	-	-	-	Correction to FR2 Spurious TC and introduction of TRP	1.0.0
2019.09		DE 195250				Measurement grid requirement Addition of Frequency Error test case to TS 38.521-2	100
	RAN5 #80 RAN5 #80	R5-185350 R5-185490	-	-	-	FR2_TxSpurious_TestConfig_38.521-2	1.0.0
	RAN5 #80	R5-185562	-	<u> -</u>	-	FR2_StoreTxRxBeamPeakCoordinates_38.521-2	1.0.0
	RAN5 #80	R5-184742	-	-	-	Update of FR2 test case 6.3.1	1.0.0
	RAN5 #80 RAN5 #80	R5-184742	-	-	-	Update of FR2 test case 6.3.3.2	1.0.0
	RAN5 #80	R5-184856	-	<u> -</u>	-	General sections updated to 38.521-2	1.0.0
	RAN5 #80	R5-185519	-	-		Updates of FR2 TRx MU and TT in Annex	1.0.0
2018-08	RAN5 #80	R5-185555	-	-	-	FR2_UE_BeamlockInvoke_38.521-2	1.0.0
2018-08	RAN5 #80	R5-185191	-	-	-	Update to Occupied Bandwidth, SEM and ACLR test cases in TS 38.521-2	1.0.0
2018-08	RAN5 #80	R5-185192	-	-	-	Update to ACS and inband blocking test cases in TS 38.521-2	1.0.0
2018-08	RAN5 #80	R5-185187	-	-	-	FR2_RefSens_TestConfig_38.521-2	1.0.0
	RAN5 #80	R5-185188	-	-	-	DL and UL RMC updated for FR2 tests	1.0.0
	RAN5 #80	R5-185189	-	-	-	Downlink physical channel updated for FR2 tests	1.0.0
	RAN5 #80	R5-185190	-	-	-	OCNG Patterns updated for FR2 tests	1.0.0
	RAN5 #80	R5-185194	-	-	-	Update to Test frequencies for SEM in TS 38.521-2	1.0.0
		R5-185196	-	-	-	Addition of Carrier Leakage test case to TS 38.521-2	1.0.0
	RAN5 #80	R5-185193	-	-	-	Addition of Annex Global In-Channel TX-Test to 38.521-2	1.0.0
	RAN5 #80	R5-185197	-	-	-	Introduction of maximum output power test cases	1.0.0
2018-08	RAN5 #80	R5-185195	-	-	-	Addition of EVM test case to TS 38.521-2	1.0.0
2018-09	RAN #81	-	-	-	-	raised to v15.0.0 with editorial changes only	15.0.0
2018-12	RAN #82	R5-186504	0021	-	F	FR2 RefSens test case updates	15.1.0
2018-12	RAN #82	R5-186505	0022	-	F	Update Text on Store Beam Peak Coordinate	15.1.0
2018-12	RAN #82	R5-186510	0023	-	F	Structure updates to Annex C and G	15.1.0
2018-12	RAN #82	R5-186675	0026	-	F	Updating test case 6.2.3 maximum output power with additional requirements	15.1.0
	RAN #82	R5-187151	0034	-	F	Updated to Annexes for FR2 tests	15.1.0
	RAN #82	R5-187152	0035	-	F	General Information updated for TS38.521-2	15.1.0
2018-12	RAN #82	R5-187561	0042	-	F	Update to Table 5.3.5-1 in TS 38.521-2	15.1.0
	RAN #82	R5-187619	0050	-	F	Update of Section 6.3.3.1 General	15.1.0
	RAN #82	R5-187838	0045	1	F	Update of transmit signal quality test cases in 38.521-2	15.1.0
2018-12	RAN #82	R5-187839	0046	1	F	Addition of In-band Emissions test case to TS 38.521-2	15.1.0
	RAN #82	R5-187840	0047	1	F	Addition of EVM equalizer spectral flatness test cases 6.4.2.4 and 6.4.2.5 to TS 38.521-2	15.1.0
2018-12	RAN #82	R5-187841	0048	1	F	Update of Common Uplink Configuration for FR2	15.1.0
	RAN #82	R5-187842	0029	1	F	General sections updated to 38.521-2	15.1.0
	RAN #82	R5-187843	0044	1	F	Update of Global In-channel Tx Test Annex in 38.521-2	15.1.0
	DANL USS	R5-187886	0020	1	F	FR2 Spurious Emission test case updates	15.1.0
2018-12	RAN #82			1	F		4540
2018-12	RAN #82 RAN #82	R5-187912	0038		Г	Addition of notes to clarify test point selection into general section of	15.1.0
2018-12 2018-12			0038 0032	1	F	TS 38.521-2 Removing the Editor's notes of SA messages and procedures for all	15.1.0
2018-12 2018-12 2018-12	RAN #82 RAN #82	R5-187912 R5-188037	0032	1	F	TS 38.521-2 Removing the Editor's notes of SA messages and procedures for all FR2 test cases	15.1.0
2018-12 2018-12 2018-12 2018-12	RAN #82	R5-187912				TS 38.521-2 Removing the Editor's notes of SA messages and procedures for all	

2018-12         RAN #82         R5-186213         OD28         1         F         Update of FR2 test case 7.4         1           2018-12         RAN #82         R5-186215         OD31         1         F         TD configuration for UE Tx test in FR2         1           2018-12         RAN #82         R5-186215         OD31         1         F         TD configuration for UE Tx test in FR2         1           2018-12         RAN #82         R5-186217         OV41         2         F         Consalignment OR to capture TS 38.101-2 updates of using RANSENRA         1           2018-12         RAN #82         R5-186217         OV41         2         Updates of MU Annex F         1           2018-13         RAN #82         R5-191091         OB8<-         F         Editorial concello of core alignment in TS 38.521-2         1           2018-13         RAN #83         R5-191091         OB8<-         F         Editorial concello of core alignment in TS 38.521-2         1           2018-13         RAN #83         R5-191091         OB8<-         F         Editorial concello of core alignment in TS 38.521-2         1           2018-03         RAN #83         R5-19107         OB8<-         F         Update to FR2 is 51.42         1         1         158.521-2		I	1		1	-		<b></b>
2016:12         RAN #82         R5-1892:14         DO2         1         F         Updates of Tim TS 38:21:2 Annex F during RANS#81         1           2016:12         RAN #82         R5-1892:16         OX31         F         TDD configuration for UET tasks in FR2         1           2016:12         RAN #82         R5-1892:16         OX31         F         TDD configuration for UET tasks in FR2         1           2016:12         RAN #82         R5-1892:17         OX41         2         F         On measurement grids           2016:12         RAN #82         R5-1802:00         OX42         2         F         Updates of TIm TS38.521:2 Annex F during RANS#NR4         1           2019:03         RAN #83         R5-1910:00         OX43         F         Editorial cleaning up of test configuration tables in TS 38.521:2         1           2019:03         RAN #83         R5-1910:00         OX44         F         Editorial cleaning up of test configuration tables in TS 38.521:2         1           2019:03         RAN #83         R5-1910:00         OX44         F         Update to FR2 test case 6.3.3 4 PRACH time mask         1           2019:03         RAN #83         R5-1910:00         OX44         F         Conton to TS 38.521-2         1         1           2		RAN #82	R5-188212	0040	2	F	Updates to maximum output power test cases	15.1.0
2016-12         RAN #82         RS-188215         0031         1         F         TD0 configuration for UE Tx test in FR2         1           2016-12         RAN #82         RS-188217         0041         2         F         Core alignment CR to capture TS 38.101-2 updates during         1           2016-12         RAN #82         RS-188218         00431         1         F         Updates of MU Annex F         1           2016-12         RAN #82         RS-188218         00431         1         F         Updates of MU Annex F         1           2019-03         RAN #83         RS-191091         00681         F         Editorial concentrol of core alignment in TS 38.521-2         1           2019-03         RAN #83         RS-191260         00861         F         Editorial concentrol of core alignment in TS 38.521-2         1           2019-03         RAN #83         RS-191670         00861         F         Update Armex Y and Annex M in TSA021-2         1           2019-03         RAN #83         RS-191670         00861         F         Update Armex Y and Annex M in TSA021-2         1           2019-03         RAN #83         RS-191670         00861         F         Update of FR2 6.3.12         1         1           2019-03						-		15.1.0
2016-12         RAN #492         RS-188216         003         1         F         Concellignment CR to capture TS 38.101-2 updates during         1           2016-12         RAN #82         RS-188217         0041         2         F         On measurement grids         1           2016-12         RAN #82         RS-168217         0044         1         T         TS 38.521-2         1           2016-12         RAN #83         RS-161092         0068         F         Updates of MU Annex F         1           2019-03         RAN #83         RS-161092         0066         F         Editorial clearcing up of test configuration tables in TS 38.521-2         1           2019-03         RAN #83         RS-16127         0067         F         Update to FR2 test case 6.3.3 4 FRACH time mask         1           2019-03         RAN #83         RS-161767         0069         F         Addition of FR2 test case 6.3.3 4 FRACH time mask         1           2019-03         RAN #83         RS-161767         0064         F         Addition of FR2 test case for 3.3 cannex         1           2019-03         RAN #83         RS-11677         0064         F         Introduction of Minimum output rown for 2UL CA         1           2019-03         RAN #83         <		RAN #82		0025	1	F		15.1.0
Control         RAN4#69         RAN4#69           2018-12         RAN #82         R5-188216         0041         1         F         Updates of MU Annex F         1           12018-12         RAN #82         R5-180216         0042         1         F         Updates of MU Annex F         1           12019-03         RAN #83         R5-19109         0084         F         Editorial corection of core alignment in T5 38521-2         1           12019-03         RAN #83         R5-19102         0084         F         Editorial corection of core alignment in T5 38521-2         1           12019-03         RAN #83         R5-19102         0086         F         Editorial corection of core alignment in T5 38521-2         1           12019-03         RAN #83         R5-19167         0069         F         State	2018-12	RAN #82	R5-188215	0031	1	F		15.1.0
2018-12         RAN #82         R5-1882/17         0041         2         F         On measurement grids         1           2018-12         RAN #82         R5-18128         0043         1         Updates of TL m TS38.521-2         1           2019-03         RAN #83         R5-191092         0084         -         F         Editorial correction of core alignment in TS 38.521-2         1           2019-03         RAN #83         R5-191022         0084         -         F         Editorial correction of core alignment in TS 38.521-2         1           2019-03         RAN #83         R5-191247         0087         -         Update to FR2 test configuration tables in TS 38.521-2         1           2019-03         RAN #83         R5-191259         0088         -         F         Update to FR2 test case 6.3.3.4 PRACH time mask         1           2019-03         RAN #83         R5-191670         0096         -         F         Update to FR2 6.4.2.4 Cobluce to the	2018-12	RAN #82	R5-188216	0039	1	F	Core alignment CR to capture TS 38.101-2 updates during	15.1.0
2016-12         RAN #62         RF-18278         0024         F         Updates of MU Annex F         1           2016-12         RAN #63         RS-191091         0083         -         F         Updates of TI in TS38.521-2 Annex F auring RANSINRA         1           2019-03         RAN #63         RS-191092         0084         -         Editorial cleaning up of test configuration tables in TS 38.521-2         1           2019-03         RAN #63         RS-191247         0085         -         F         Editorial cleaning up of test configuration tables in TS 38.521-2         1           2019-03         RAN #63         RS-191507         0080         -         F         Pudate to RPL test case 6.3.3.4 PRACH time mask         1           2019-03         RAN #63         RS-191676         00904         -         F         Shared Risk clarification in TS 38.521-2         1           2019-03         RAN #63         RS-191676         00964         -         F         Addition of FR2 6.3.1 Clanum Output power         1           2019-03         RAN #63         RS-191670         0096         -         F         Addition of FR2 6.3.2 Clanum Output power         1           2019-03         RAN #63         RS-191690         0099.         -         F         Indditi							RAN4#89	
2016-12         RAN #62         RF-18278         0024         F         Updates of MU Annex F         1           2016-12         RAN #63         RS-191091         0083         -         F         Updates of TI in TS38.521-2 Annex F auring RANSINRA         1           2019-03         RAN #63         RS-191092         0084         -         Editorial cleaning up of test configuration tables in TS 38.521-2         1           2019-03         RAN #63         RS-191247         0085         -         F         Editorial cleaning up of test configuration tables in TS 38.521-2         1           2019-03         RAN #63         RS-191507         0080         -         F         Pudate to RPL test case 6.3.3.4 PRACH time mask         1           2019-03         RAN #63         RS-191676         00904         -         F         Shared Risk clarification in TS 38.521-2         1           2019-03         RAN #63         RS-191676         00964         -         F         Addition of FR2 6.3.1 Clanum Output power         1           2019-03         RAN #63         RS-191670         0096         -         F         Addition of FR2 6.3.2 Clanum Output power         1           2019-03         RAN #63         RS-191690         0099.         -         F         Indditi	2018-12	RAN #82	R5-188217	0041	2	F	On measurement grids	15.1.0
2019-12         RAN #82         RF-182736         0024         2         F         Updates of TL in TS38.521-2         Annex F         uning RANSINRA         1           2019-03         RAN #83         R5.191092         0084         -         F         Editorial correction of core alignment in TS 38.521-2         1           2019-03         RAN #83         R5.191022         0086         -         F         Editorial correction of core alignment in TS 38.521-2         1           2019-03         RAN #83         R5.191259         0088         -         F         Update to FR2 test case 6.3.3.4 PRACH time mask         1           2019-03         RAN #83         R5.191570         00090         -         Shared Rakk calmification in TS 38.521-2         1           2019-03         RAN #83         R5.191670         0008         -         F         Update of FR2 6.3.2.4 DNOLeve time mask         1           2019-03         RAN #83         R5.191670         0006         -         F         Addition of PR2 6.3.4.2 DNOLeve power tolerance         1           2019-03         RAN #83         R5.191670         0008         -         F         Update of FR2 6.3.4.2 DNOLeve power tolerance         1           2019-03         RAN #83         R5.191824         10102	2018-12	RAN #82	R5-188218	0043	1	F		15.1.0
2019-03         RAN #83         RE-191091         (D08)         .         F         Updates of T1 in TS38.521-2 2ncs.         1           2019-03         RAN #83         RE-191092         (D08)         .         F         Editorial cleaning up of test configuration tables in TS 38.521-2         1           2019-03         RAN #83         RE-191240         (D08)         .         F         Update TRP messurement procedure Annex in TS38.521-2         1           2019-03         RAN #83         RE-191247         (D08)         .         F         Lupdate Annex K and Annex M in TS38.521-2         1           2019-03         RAN #83         RE-191697         (D09)         .         F         Shared Risk clanification in TS 38.521-2         1           2019-03         RAN #83         RE-191676         (D09)         .         F         Cladition of FR2.6.3.1 (Minum Output power 1         1           2019-03         RAN #83         RE-191676         (D09)         .         F         Lupdate of FR2.6.3.1 (Minum Output power 10         1           2019-03         RAN #83         RE-191679         (D09)         .         F         Lupdate of PR2.6.3.2 (Minum Output power 10         1           2019-03         RAN #83         RE-191812         (D100)         .				0024	2	F		15.1.0
2019-03         RAN #83         R5-191022         0084         -         F         Editorial correction of core alignment in TS 38.521-2         1           2019-03         RAN #83         R5-191240         0086         -         F         Update TRP measurement procedure Annex in TS38.521-2         1           2019-03         RAN #83         R5-191250         0088         -         F         Update TRP measurement procedure Annex in TS38.521-2         1           2019-03         RAN #83         R5-191250         0088         -         F         Update to FR2 to S3.45 PRACH time mask         1           2019-03         RAN #83         R5-191670         0090         -         S         Stared Risk clarification to TS38.521-2         1         1           2019-03         RAN #83         R5-191670         0096         -         F         Addition of RF2 6.3.4 2 DRACH time mask         1           2019-03         RAN #83         R5-191870         0096         -         F         Addition of RF2 6.3.4 2 DRACH time mask         1           2019-03         RAN #83         R5-191870         0096         -         F         Addition of RF2 6.3.2 Cabenuity Drover for ULC A         1           2019-03         RAN #83         R5-191800         0097         -					-	-		15.2.0
2019-03         RAN #83         R5-19103         0008         -         F         Editorial cleaning up of test configuration tables in TS 38,521-2         1           2019-03         RAN #83         R5-191247         0087         -         F         Update Annex K and Annex K in TS38,521-2         1           2019-03         RAN #83         R5-191267         0080         -         F         Update Annex K and Annex K in TS38,521-2         1           2019-03         RAN #83         R5-191607         0090         -         F         Shared Risk clarification in TS 38,521-2         1           2019-03         RAN #83         R5-191676         0094         -         F         Addition of FR2.6.2.4 Configured transmitted power         1           2019-03         RAN #83         R5-191677         0096         -         F         Update of FR2.6.3.1 Minimum Output power tolerance         1           2019-03         RAN #83         R5-191670         0096         -         F         Update of RP2.6.3.1 Animum Output power tolerance         1           2019-03         RAN #83         R5-191670         0066         -         F         Addition of FR2.6.3.1 Animum Output power tolerance         1         1           2019-03         RAN #83         R5-191680 <td< td=""><td></td><td></td><td></td><td></td><td>-</td><td>-</td><td></td><td></td></td<>					-	-		
2019-03         RAN #83         R5-191246         D086         -         F         Update TRP measurement procedure Annex K and Annex					-	-		15.2.0
2019-03         RAN #83         R5-191247         0087         -         F         Update Annex K and Annex M in TS38.521-2         1           2019-03         RAN #83         R5-191507         0090         -         F         Update to FR2 test cases         3.3.4 PRACH Hime mask         1           2019-03         RAN #83         R5-191676         0094         -         F         CR to TS3.521-2         1         1           2019-03         RAN #83         R5-191676         0094         -         F         Addition of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191690         0096         -         F         Addition of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191690         0096         -         F         F         Vogdate fR2 6.3.4 Absolute power tolerance         1           2019-03         RAN #83         R5-191820         0100         -         F         F         R2 purptuse fraitsoin tost case updates         1         1         1         1         1         1         1         1         1         1         1         1         1         1         1         1         1         1         1         <					-	-		15.2.0
2019-03         RAN #83         R5-191259         0088         -         F         Update to FR2 test case 6.3.3.4 PRACH time mask         1           2019-03         RAN #83         R5-191607         00903         -         F         Shared Risk clanification in TS 38.521-2         1           2019-03         RAN #83         R5-191670         0095         -         F         Addition of FR2 6.3.4 Configured transmitted power         1           2019-03         RAN #83         R5-191670         0096         -         F         Update of FR2 6.3.4 Zabsolute power toterance         1           2019-03         RAN #83         R5-191690         0099         -         F         Update of FR2 6.3.3.2 General ON/OFF time mask         1           2019-03         RAN #83         R5-19180         0099         -         F         Oddate of Annex					-	_		15.2.0
2019-03         RAN #83         R5-191007         D090         -         F         CR to 753 8521-2         1           2019-03         RAN #83         R5-191676         D094         -         F         CR to 753 8521-2         0         1           2019-03         RAN #83         R5-191676         D096         -         F         Addition of FR2 6.3.4 Addition more provement of the mask         1           2019-03         RAN #83         R5-191793         D096         -         F         Addition of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191793         D099         -         F         PC 2bynouse Emission DNC abs.21-2         1           2019-03         RAN #83         R5-191806         D102         -         F         RAS purlouse Emission DNC abs.21-2         1           2019-03         RAN #83         R5-191806         D102         -         F         Instructuon of Annex on Characteristics of the Interfering Signal         1           2019-03         RAN #83         R5-192020         D111         -         F         To stimode and test topo function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192050         D111         -         F <td></td> <td></td> <td></td> <td></td> <td>-</td> <td>F</td> <td></td> <td>15.2.0</td>					-	F		15.2.0
2019-03         RAN #83         R5-191670         0093         -         F         CR to TS 38.521-2 to add text proposal for Amamited power         1           2019-03         RAN #83         R5-191677         0095         -         F         Undiato of FR2 6.3.1 Minimum Output Power         1           2019-03         RAN #83         R5-191670         0096         -         F         Undiato of FR2 6.3.2 A 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191670         0096         -         F         Undiato of FR2 6.3.2 C and A 2 Absolute power for 2UL CA         1           2019-03         RAN #83         R5-191809         0099         -         F         Undiate of FR2 6.3.2 C and Annex L         1           2019-03         RAN #83         R5-191804         0102         -         F         Undiate to Annex K and Annex L         1           2019-03         RAN #83         R5-191804         0107         -         F         Test mode and test loop function activation in SA Tx RF test cases         1         in TS 38.521-2         1         i	2019-03		R5-191259	8800	-	F	Update to FR2 test case 6.3.3.4 PRACH time mask	15.2.0
2019-03         RAN #83         R5-191676         0094         -         F         Addition of R22 6.3.4 Configured transmitted power         1           2019-03         RAN #83         R5-191670         0096         -         F         Addition of R22 6.3.4 2 Absolute power toterance         1           2019-03         RAN #83         R5-191680         0097         -         F         Addition of R22 6.3.4 2 Absolute power for 2UL CA         1           2019-03         RAN #83         R5-191690         0098         -         F         Introduction of Minimum output power for 2UL CA         1           2019-03         RAN #83         R5-191824         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-192092         0110         -         F         Tost mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192092         0110         -         F         Tost mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192050         0111         -         F         Test mode and test loop function activation in Agregate power tolerance in 38.521-2         1           2019-03         RAN #83	2019-03	RAN #83	R5-191507	0090	-	F	Shared Risk clarification in TS 38.521-2	15.2.0
2019-03         RAN #83         R5-191677         0095         -         F         Addition of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191680         0097         -         F         Updite of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191690         0099         -         F         Updite of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191812         0100         -         F         Update for 36.521-2         1           2019-03         RAN #83         R5-191824         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-191864         0107         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192052         0111         -         F         Test mode and test loop function activation in SA RX RF test cases         1           2019-03         RAN #83         R5-192050         0091         F         Update of test case 6.4.3. Relative power tolerance in 36.521-2         1           2019-03         RAN #83         R5-192450         0092         1         <	2019-03	RAN #83	R5-191609	0093	-	F	CR to TS 38.521-2 to add text proposal for Annex F.1	15.2.0
2019-03         RAN #83         R5-191677         0095         -         F         Addition of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191680         0097         -         F         Update of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191690         0099         -         F         Update of FR2 6.3.4 2 Absolute power tolerance         1           2019-03         RAN #83         R5-191812         0100         -         F         Update for 36.521-2         1           2019-03         RAN #83         R5-191824         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-192052         0110         -         F         Test mode and test loop function activation in SA Tx RF test cases         1         in TS 38.521-2         1           2019-03         RAN #83         R5-192052         0111         -         F         Lydate of Global in-channel Tx Test Annex for R2         1           2019-03         RAN #83         R5-1922450         0089         1         F         Lydate of Global in-channel Tx Test Annex for R2         1           2019-03         RAN #83         R5-192450	2019-03		R5-191676	0094	-	F		15.2.0
2019-03         RAN #83         R5-191629         OO96         -         F         Addition of FR2 6.3.42 Absolute power tolerance         1           2019-03         RAN #83         R5-191793         OO98         -         F         Introduction of Minimum output power for 2UL CA         1           2019-03         RAN #83         R5-191812         O100         -         F         FR2 Spurious Emission test case updates         1           2019-03         RAN #83         R5-191824         O102         -         F         Hordouction of Amex to Characteristics of the Interfering Signal         1           2019-03         RAN #83         R5-192092         O110         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192092         O110         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192192         O111         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192450         O089         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03					-			15.2.0
2019-03         RAN #83         R5-191680         0097         -         F         Introduction of Minimum output power for 2UL CA         1           2019-03         RAN #83         R5-191809         0099         -         F         OBW test procedure update for 36.521-2         1           2019-03         RAN #83         R5-191812         0100         -         F         DBW test procedure update for 36.521-2         1           2019-03         RAN #83         R5-191862         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-191986         0107         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192092         0111         -         F         Test mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of test case 5.4.3. Relative power tolerance in 35.521-2         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of test environment for frequency error         1           2019-03         RAN #83         R5-192450         00161 <td></td> <td></td> <td></td> <td></td> <td>l</td> <td>•</td> <td></td> <td>15.2.0</td>					l	•		15.2.0
2019-03         RAN #83         R5-191793         0008         -         F         Introduction of Minimum output power for 2UL CA         1           2019-03         RAN #83         R5-191809         0090         -         F         OBW test procedure update for 38.521-2         1           2019-03         RAN #83         R5-191824         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-191826         0107         -         F         Untroduction of Annex K and Annex L         1           2019-03         RAN #83         R5-192020         0110         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192020         0111         -         F         Test mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192020         0105         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         1005         1         F         Update of Intest environment for frequency error         1           2019-03         RAN #83         R5-192640         1016         1<						-		15.2.0
2019-03         RAN #83         RS-191824         0102         -         F         OBW test procedure update for 38.521-2         1           2019-03         RAN #83         RS-191824         0102         -         F         FR2 Spurious Emission test case updates         1           2019-03         RAN #83         RS-191824         0102         -         F         FR2         1           2019-03         RAN #83         RS-191824         0102         -         F         Introduction of Annex on Characteristics of the Interfering Signal         1           2019-03         RAN #83         RS-192092         0111         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         RS-192450         0082         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         RS-192451         0082         1         F         Update of tast asse 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03         RAN #83         RS-192451         0082         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         RS-192648         0101         1<					<u> </u>	-		
2019-03         RAN #83         R5-191812         0100         -         F         FV2 dudate to Annex K and Annex L         1           2019-03         RAN #83         R5-19186         0107         -         F         Indroduction of Annex on Characteristics of the Interfering Signal FR2         1           2019-03         RAN #83         R5-192092         0110         -         F         Test mode and test loop function activation in SA Tx RF test cases in TS 38.521-2           2019-03         RAN #83         R5-192022         0111         -         F         Test mode and test loop function activation in SA Rx RF test cases in TS 38.521-2           2019-03         RAN #83         R5-192420         0108         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192451         0089         1         F         Update of Global In-channel Tx Test Annex for R2         1           2019-03         RAN #83         R5-192454         0106         1         F         Indates of first environment for frequency rent loterance in RS AFR2         1           2019-03         RAN #83         R5-192649         0117         1         F         Update OS Hites case in TS 38.521-2         1           2019-03         RAN #83         R5-					-	-		15.2.0
2019-03         RAN #83         R5-191824         0102         -         F         Update to Annex K and Annex L         1           2019-03         RAN #83         R5-191986         0107         -         F         Introduction of Annex on Characteristics of the Interfering Signal         1           2019-03         RAN #83         R5-192092         0110         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192020         0111         -         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of test case 6.3.4.3, Relative power tolerance in NS 6.521-2         1           2019-03         RAN #83         R5-192640         0106         1         F         RR2 SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192640         0106         1         F         RC2 SA Spurious Emission Coexistence in NR SA FR2         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test case for FR2         1           2019-03         RAN #83					-	-		15.2.0
2019-03         RAN #83         R5-191986         0107         F         Introduction of Annex on Characteristics of the Interfering Signal         1           2019-03         RAN #83         R5-192092         0110         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192209         0111         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of clobal In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of clobal In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192452         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192649         0111         1         F         Update SM treat sase for S3 & 521-2         1           2019-03         RAN #83         R5-192650         0114         1         F         Update SM treat sase in TS 3& 521-2         1           2019-03         RAN #83         R5-192651         0114         1 <t< td=""><td></td><td></td><td></td><td></td><td> -</td><td>-</td><td></td><td>15.2.0</td></t<>					-	-		15.2.0
FR2         FR2           2019-03         RAN #83         R5-192092         0110         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192095         0111         F         Test mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192450         0082         1         F         Update of test case 6.3.4.3. Relative power tolerance in 38.521-2         1           2019-03         RAN #83         R5-192451         0082         1         F         Update of test case 6.3.4.3. Relative power tolerance in NS 8.521-2         1           2019-03         RAN #83         R5-192640         0161         1         F         RRA #83         R5-192651         111         1         C Nodato ULROC for 60kH2 SCS in Annex A.2.3         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test cases for R2         1           2019-03         RAN #83         R5-192650         0114         1         F         Update of transmit signal quality test case for R2         1           2019-03         RAN #83         R5-192650         0114         1         F         Update of An					-	-		15.2.0
2019-03         RAN #83         R5-192092         0110         F         Test mode and test loop function activation in SA Tx RF test cases         1           2019-03         RAN #83         R5-192095         0111         F         Test mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         0089         1         F         Updates of test environment for frequency error         1           2019-03         RAN #83         R5-192452         0105         1         F         FR2 SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192640         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192640         0111         1         F         Update of tunck to Cock set case         1         3.821-2         1           2019-03         RAN #83         R5-192650         0111         1         F         Update SEM test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0	2019-03	RAN #83	R5-191986	0107	-	F	Introduction of Annex on Characteristics of the Interfering Signal	15.2.0
In TS 38.521-2         In TS 38.521-2           2019-03         RAN #83         R5-192095         0111         -         F         Test mode and test loop function activation in SA Rx RF test cases         1.           2019-03         RAN #83         R5-192122         0112         -         F         Update of Elest case 6.3.4.3, Relative power tolerance in 38.521-2         1.           2019-03         RAN #83         R5-192451         0082         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1.           2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1.           2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1.           2019-03         RAN #83         R5-192651         0114         1         F         Update OW test case in TS 38.521-2         1.           2019-03         RAN #83         R5-192652         0115         1         Update SC Mest case in TS 38.521-2         1.           2019-03         RAN #83         R5-192653         0114         1         F         Update SC Mest case in TS 38.521-2         1.								
2019-03         RAN #83         R5-192095         0111         -         F         Test mode and test loop function activation in SA Rx RF test cases         1           2019-03         RAN #83         R5-192122         0112         -         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         0089         1         F         Update of test environment for frequency error         1           2019-03         RAN #83         R5-192452         0105         1         F         FR2 SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192650         0115         1         F         Update SEM test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0116         1         F         LPdate SEM test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0104         <	2019-03	RAN #83	R5-192092	0110	-	F	Test mode and test loop function activation in SA Tx RF test cases	15.2.0
In TS 38.521-2         In TS 38.521-2           2019-03         RAN #83         R5-192450         0089         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         0082         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03         RAN #83         R5-192450         1005         1         F         PR2 SA Synious Emission Coexistence test case         1           2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192650         0116         1         F         Update OW test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0116         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192667							in TS 38.521-2	
In TS 38.521-2         In TS 38.521-2           2019-03         RAN #83         R5-192450         0089         1         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-03         RAN #83         R5-192450         0082         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03         RAN #83         R5-192450         1005         1         F         PR2 SA Synious Emission Coexistence test case         1           2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192650         0116         1         F         Update OW test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0116         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192667	2019-03	RAN #83	R5-192095	0111	-	F	Test mode and test loop function activation in SA Rx RF test cases	15.2.0
2019-03         RAN #83         R5-192450         0089         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03         RAN #83         R5-192451         0082         1         F         Updates of test environment for frequency error         1           2019-03         RAN #83         R5-192640         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192640         0111         1         F         Detate of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         1           2019-03         RAN #83         R5-192651         0116         1         F         Update ACLR test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0101         1         F         FR2 Reference Sensitivity test case updates         1           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192680         0080         2         F								
2019-03         RAN #83         R5-192450         0089         1         F         Update of test case 6.3.4.3, Relative power tolerance in 38.521-2         1           2019-03         RAN #83         R5-192452         0105         1         F         IP2A SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192640         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192640         0111         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         1           2019-03         RAN #83         R5-192652         0115         1         F         Update ACLR test case in TS 38.521-2         1           2019-03         RAN #83         R5-192650         0101         1         F         FR2 Reference Sensitivity test case updates         1           2019-03         RAN #83         R5-192640         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192640         0080         2         F	2019-03	RAN #83	R5-192122	0112	-	F		15.2.0
2019-03         RAN #83         R5-192451         0082         1         F         Updates of test environment for frequency error         1           2019-03         RAN #83         R5-192452         0105         1         F         FR2 SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192649         0117         1         F         CR to add UL RMC for 60kHz SCs in Annex A.2.3         1           2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test case for FR2         1           2019-03         RAN #83         R5-192651         0114         1         F         Update of transmit signal quality test case for FR2         1           2019-03         RAN #83         R5-192652         0115         1         F         Update of transmit signal quality test case for S3.521-2         1           2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity test case in TS 38.521-2         1           2019-03         RAN #83         R5-192640         0101         1         F         Updates of Tin TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192640         01081 <td></td> <td></td> <td></td> <td></td> <td>1</td> <td></td> <td></td> <td>15.2.0</td>					1			15.2.0
2019-03         RAN #83         R5-192452         0105         1         F         FR2 SA Spurious Emission Coexistence test case         1           2019-03         RAN #83         R5-192644         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1           2019-03         RAN #83         R5-192640         0117         1         F         CR to add UL RMC for 60kHz SCS in Annex A.2.3         1           2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         1           2019-03         RAN #83         R5-192653         0116         1         F         Update ACLR test case in TS 38.521-2         1           2019-03         RAN #83         R5-192654         0101         1         F         FR2 Reference Sensitivity test case updates         1           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192667         0108         1         F         Updates of Ti In TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192849         0080         2         F         Updates of MU						_		15.2.0
2019-03         RAN #83         R5-192648         0106         1         F         Introduction of Aggregate power tolerance in NR SA FR2         1.           2019-03         RAN #83         R5-192660         0113         1         F         CR to add UL RMC for 60kHz CSC sin Annex A.2.3         1.           2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         1.           2019-03         RAN #83         R5-192652         0115         1         F         Update ACLR test case in TS 38.521-2         1.           2019-03         RAN #83         R5-192654         0101         1         F         FQ2 Reference Sensitivity test case updates         1.           2019-03         RAN #83         R5-192655         0104         1         F         FQ2 Reference Sensitivity test case updates         1.           2019-03         RAN #83         R5-192640         0108         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192843         0080         2         F         Updates of Tin TS38.521-2 Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192843         0081         2 <t< td=""><td></td><td></td><td></td><td></td><td>-</td><td></td><td></td><td>15.2.0</td></t<>					-			15.2.0
2019-03         RAN #83         R5-192650         0113         1         F         CR to add UL RMC for 60kHz SCS in Annex A.2.3         1           2019-03         RAN #83         R5-192651         0113         1         F         Update of transmit signal quality test cases for FR2         1           2019-03         RAN #83         R5-192651         0116         1         F         Update OBV test case in TS 38.521-2         1           2019-03         RAN #83         R5-192653         0116         1         F         Update ACLR test case in TS 38.521-2         1           2019-03         RAN #83         R5-192653         0104         1         F         FR2 Reference Sensitivity test case updates         1           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192640         0080         2         F         Updates of M1 in TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192640         0118         4         F         Updates of M1 in TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192640         0113         1         F         38.521-2 Cin						_	· · ·	
2019-03         RAN #83         R5-192650         0113         1         F         Update of transmit signal quality test cases for FR2         1.           2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         1.           2019-03         RAN #83         R5-192653         0116         1         F         Update SEM test case in TS 38.521-2         1.           2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity test case updates         1.           2019-03         RAN #83         R5-192667         0108         1         F         R2 Reference Sensitivity test case updates         1.           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1.           2019-03         RAN #83         R5-192660         0103         1         F         38.521-2         Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192640         0081         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192640         0113         F         2.         E ditoria								15.2.0
2019-03         RAN #83         R5-192651         0114         1         F         Update OBW test case in TS 38.521-2         11           2019-03         RAN #83         R5-192652         0115         1         F         Update ACLR test case in TS 38.521-2         11           2019-03         RAN #83         R5-192654         0101         1         F         FR2 Reference Sensitivity test case updates         11           2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity test case updates         11           2019-03         RAN #83         R5-192650         0108         1         F         Update of Annex F.2         11           2019-03         RAN #83         R5-192640         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192640         0103         1         F         38.521-2 Editor's Note Updates         12         2019-03         RAN #83         R5-192640         0103         1         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         11           2019-03         RAN #83         R5-192640         0113         -         F         Correction of 38.521-2 <t< td=""><td></td><td></td><td></td><td></td><td></td><td>-</td><td></td><td>15.2.0</td></t<>						-		15.2.0
2019-03         RAN #83         R5-192652         0115         1         F         Update SEM test case in TS 38.521-2         1           2019-03         RAN #83         R5-192653         0116         1         F         Update ACLR test case in TS 38.521-2         1           2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity EIS spherical coverage         1           2019-03         RAN #83         R5-192657         0108         1         F         Update of Annex F.2         1           2019-03         RAN #83         R5-192640         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192640         0081         2         F         Updates of TL in TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192640         0118         4         F         Updates to maximum output power test cases         1           2019-03         RAN #83         R5-192640         0131         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         1           2019-06         RAN#84         R5-193541         0137         F         Alignment of RAN44 pending issues in TS 38						-		15.2.0
2019-03         RAN #83         R5-192653         0116         1         F         Update ACLR test case in TS 38.521-2         11           2019-03         RAN #83         R5-192654         0101         1         F         FR2 Reference Sensitivity test case updates         11           2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity test case updates         11           2019-03         RAN #83         R5-192647         0108         1         F         Update of Annex F.2         11           2019-03         RAN #83         R5-192640         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192640         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         R5-192680         0103         1         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         11           2019-03         RAN#83         R5-192641         0137         -         -         -         Editorial correction of 78.521-2 Annex         120.8.521-2         11           2019-06         RAN#84         R5-193575         0143         -						-		15.2.0
2019-03         RAN #83         R5-192654         0101         1         F         FR2 Reference Sensitivity test case updates         11           2019-03         RAN #83         R5-192655         0108         1         F         FR2 Reference Sensitivity EIS spherical coverage         11           2019-03         RAN #83         R5-192649         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192640         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN#83         R-192680         0137         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193521         0138         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-193575         0143         -         F		RAN #83	R5-192652		1	F		15.2.0
2019-03         RAN #83         R5-192655         0104         1         F         FR2 Reference Sensitivity EIS spherical coverage         1.           2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         1.           2019-03         RAN #83         R5-192849         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192840         0081         2         F         Updates of TT in TS38.521-2 Annex F during RAN5#82         1.           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         1.           2019-03         RAN #83         R5-192680         0118         4         F         Updates to maximum output power test cases         1.           2019-06         RAN#83         R5-193541         0137         -         E         Alignment of scheduling of DL RMC with scheduling of UL RMC         1.           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         1.           2019-06         RAN#84         R5-193749         0151         -         F         Updates of AC	2019-03	RAN #83	R5-192653	0116	1	F	Update ACLR test case in TS 38.521-2	15.2.0
2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         11           2019-03         RAN #83         R5-192849         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192843         0081         2         F         Updates of TT in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192840         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         RP-190746         0118         4         F         Updates to maximum output power test cases         11           2019-06         RAN#84         R5-193552         0138         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193552         0138         -         F         Correation of 38.521-2 7.4         11           2019-06         RAN#84         R5-193620         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194243         0161         -         F <td< td=""><td>2019-03</td><td>RAN #83</td><td>R5-192654</td><td>0101</td><td>1</td><td>F</td><td>FR2 Reference Sensitivity test case updates</td><td>15.2.0</td></td<>	2019-03	RAN #83	R5-192654	0101	1	F	FR2 Reference Sensitivity test case updates	15.2.0
2019-03         RAN #83         R5-192667         0108         1         F         Update of Annex F.2         11           2019-03         RAN #83         R5-192849         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192843         0081         2         F         Updates of TT in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192840         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         RP-190746         0118         4         F         Updates to maximum output power test cases         11           2019-06         RAN#84         R5-193552         0138         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193552         0138         -         F         Correation of 38.521-2 7.4         11           2019-06         RAN#84         R5-193620         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194243         0161         -         F <td< td=""><td>2019-03</td><td>RAN #83</td><td>R5-192655</td><td>0104</td><td>1</td><td>F</td><td>FR2 Reference Sensitivity EIS spherical coverage</td><td>15.2.0</td></td<>	2019-03	RAN #83	R5-192655	0104	1	F	FR2 Reference Sensitivity EIS spherical coverage	15.2.0
2019-03         RAN #83         R5-192849         0080         2         F         Updates of MU in TS38.521-2 Annex F during RAN5#82         1           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         RF-190746         0118         4         F         Updates to maximum output power test cases         11           2019-03         RAN#83         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193552         0138         -         F         Core alignment of RAN4 pending issues in TS 38.521-2         11           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2         7.4         11           2019-06         RAN#84         R5-193620         0152         -         F         Correction of 38.521-2         clause 2 to 5         11           2019-06         RAN#84         R5-194263         0161         -         F         Add	2019-03	RAN #83		0108	1	F		15.2.0
2019-03         RAN #83         R5-192843         0081         2         F         Updates of TT in TS38.521-2 Annex F during RAN5#82         11           2019-03         RAN #83         R5-192680         0103         1         F         38.521-2 Editor's Note Updates         11           2019-03         RAN #83         RP-190746         0118         4         F         Updates to maximum output power test cases         11           2019-03         RAN#83         R-190746         0118         4         F         Updates to maximum output power test cases         12           2019-06         RAN#84         R5-19352         0138         -         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         11           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-19320         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194263         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         12           2019-06         RAN#84         R5-194264         0163         -         F         Corr								15.2.0
2019-03         RAN #83         R5-192680         0103         1         F         38.521-2         Editori's Note Updates         1           2019-03         RAN #83         RP-190746         0118         4         F         Updates to maximum output power test cases         11           2019-03         RAN#83         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193552         0138         -         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         12           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193749         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194204         0163         -         F         R2 Reference Sensitivity test case updates         12           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIS								15.2.0
2019-03         RAN #83         RP-190746         0118         4         F         Updates to maximum output power test cases         11           2019-03         RAN#83         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         11           2019-06         RAN#84         R5-193541         0137         -         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         11           2019-06         RAN#84         R5-193552         0143         -         F         Correction of 38.521-2.7.4         11           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193749         0151         -         F         Correction of 38.521-2.7.4         11           2019-06         RAN#84         R5-194203         0161         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Update of 6.2.3 A-MPR FR2         1					-	_		15.2.0
2019-03         RAN#83         -         -         -         Editorial correction of references to TS 38.508-1 clause 4.6 tables         1           2019-06         RAN#84         R5-193541         0137         -         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         1           2019-06         RAN#84         R5-193552         0138         -         F         Correction of 38.521-2 7.4         1           2019-06         RAN#84         R5-193759         0143         -         F         Correction of 38.521-2 7.4         1           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         1           2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         1           2019-06         RAN#84         R5-194209         0163         -         F         Correction to FR2 EIRP test configurations         1           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         1           2019-06         RAN#84         R5-194269         0164         -         F         Update FR2 ACS and Inband blocking test cases					_			
2019-06         RAN#84         R5-193541         0137         -         F         Alignment of scheduling of DL RMC with scheduling of UL RMC         11           2019-06         RAN#84         R5-193552         0138         -         F         Core alignment of RAN4 pending issues in TS 38.521-2         11           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194209         0153         -         F         RAVER Reference Sensitivity test case updates         12           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIR test configurations         12           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         12           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 AC			RP-190746	0118	4	F		15.2.0
2019-06         RAN#84         R5-193552         0138         -         F         Core alignment of RAN4 pending issues in TS 38.521-2         11           2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-1940618         0171         -         F         Update of Global In-channe			-	-	-	-		15.2.0
2019-06         RAN#84         R5-193575         0143         -         F         Correction of 38.521-2 7.4         11           2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194268         0171         -         F         Update of Global In-channe					-			15.3.0
2019-06         RAN#84         R5-193749         0151         -         F         Updates of ACLR test procedure         11           2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194968         0167         1         F         Upd					-	-		15.3.0
2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194968         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1 <td< td=""><td>2019-06</td><td>RAN#84</td><td>R5-193575</td><td>0143</td><td><u> -</u></td><td>F</td><td></td><td>15.3.0</td></td<>	2019-06	RAN#84	R5-193575	0143	<u> -</u>	F		15.3.0
2019-06         RAN#84         R5-193820         0152         -         F         Correction of 38.521-2 clause 2 to 5         11           2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194968         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1 <td< td=""><td>2019-06</td><td>RAN#84</td><td>R5-193749</td><td>0151</td><td> -</td><td>F</td><td>Updates of ACLR test procedure</td><td>15.3.0</td></td<>	2019-06	RAN#84	R5-193749	0151	-	F	Updates of ACLR test procedure	15.3.0
2019-06         RAN#84         R5-194009         0153         -         F         FR2 Reference Sensitivity test case updates         11           2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         11           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F					-			15.3.0
2019-06         RAN#84         R5-194243         0161         -         F         Addition FR2 blocking measurement procedure in Annex K         1           2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         1           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         1           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         1           2019-06         RAN#84         R5-194618         0170         -         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         1           2019-06         RAN#84         R5-194958         0139         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         1           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         1           2019-06         RAN#84         R5-194970         0160         1         F					-	F		15.3.0
2019-06         RAN#84         R5-194264         0163         -         F         Correction to FR2 EIRP test configurations         11           2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-19461         0170         -         F         Update to 6.2.3 A-MPR FR2         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam corresp					-	_		15.3.0
2019-06         RAN#84         R5-194265         0164         -         F         Correction to FR2 EIS test configurations         11           2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194461         0170         -         F         Update to 6.2.3 A-MPR FR2         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194970         0162         1         F         Introduction of beam					-			15.3.0
2019-06         RAN#84         R5-194269         0165         -         F         Update FR2 ACS and Inband blocking test cases         11           2019-06         RAN#84         R5-194461         0170         -         F         Update to 6.2.3 A-MPR FR2         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error					Ľ.	-	°	15.3.0
2019-06         RAN#84         R5-194461         0170         -         F         Update to 6.2.3 A-MPR FR2         11           2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194968         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         11           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.					F	_		
2019-06         RAN#84         R5-194618         0171         -         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of Global In-channel Tx Test Annex for FR2         11           2019-06         RAN#84         R5-194958         0139         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         11           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194970         0162         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         11           2019-06         RAN#84         R5-194977         0175         1         F         Editorial correcti						-		15.3.0
2019-06         RAN#84         R5-194958         0139         1         F         Updates of MU and TT in TS 38.521-2 Annex F during RAN5#NR5         13           2019-06         RAN#84         R5-194968         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         14           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         14           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         14           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         14           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         14           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         14           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         14           2019-06         RAN#84         R5-195080         0176         -         F         Up						-		15.3.0
2019-06         RAN#84         R5-194968         0167         1         F         Update of TC 6.3A.1.1 Minimum output power for 2UL CA         1           2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         1           2019-06         RAN#84         R5-194970         0160         1         F         Clean up FR2 SA test cases         1           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         1           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         1           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         1					-			15.3.0
2019-06         RAN#84         R5-194969         0166         1         F         Clean up FR2 SA test cases         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         11           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence for CA         11           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         11           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         11           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         11					-			15.3.0
2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence for CA         1           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         1           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         1           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         1		RAN#84	R5-194968	0167	1	F		15.3.0
2019-06         RAN#84         R5-194970         0160         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence         1           2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence for CA         1           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         1           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         1           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         1	2019-06	RAN#84	R5-194969	0166	1	F	Clean up FR2 SA test cases	15.3.0
2019-06         RAN#84         R5-194971         0162         1         F         Introduction of beam correspondence for CA         1           2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         1           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         1           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         1					1	F		15.3.0
2019-06         RAN#84         R5-194976         0173         1         F         Update of Frequency Error Test Case for FR2         1           2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         1           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         1								15.3.0
2019-06         RAN#84         R5-194977         0175         1         F         Editorial corrections for 6.2.1 UE maximum output power         12           2019-06         RAN#84         R5-195080         0176         -         F         Update of FR2 ON_ON time mask test cases         12						_		15.3.0
2019-06 RAN#84 R5-195080 0176 - F Update of FR2 ON_ON time mask test cases 11					-	_		15.3.0
					-			
					-			15.3.0
								15.3.0
2019-06 RAN#84 R5-195149 0142 1 F Correction of 38.521-2 6.3.2	2019-06	KAN#84	K5-195149	0142	1	F	Correction of 38.521-2 6.3.2	15.3.0

2019-06	RAN#84	R5-195151	0144	1	F	Introduction of MOP (SA UL CA)	15.3.0
	RAN#84	R5-195151	0145	1	F	Introduction of OFF power (SA UL CA)	15.3.0
	RAN#84	R5-195153	0146	1	F	Introduction of Frequency error (SA UL CA)	15.3.0
	RAN#84	R5-195154	0148	1	F	Introduction of SEM (SA UL CA)	15.3.0
	RAN#84	R5-195155	0149	1	F	Introduction of ACLR (SA UL CA)	15.3.0
	RAN#84	R5-195156	0150	1	F	Introduction of General Spurious (SA UL CA)	15.3.0
	RAN#84	R5-195157	0157	1	F	Introduction of New test case 6.5A.1.1 Occupied bandwidth for CA (2UL CA)	15.3.0
2019-06	RAN#84	R5-195158	0156	1	F	Update Out of band emission test cases in TS 38.521-2	15.3.0
	RAN#84	R5-195160	0159	1	F	Introduction of SRS time mask for UL-MIMO	15.3.0
	RAN#84	R5-195404	0172	1	F	Update of transmit signal quality test cases for FR2	15.3.0
	RAN#84	R5-195417	0154	1	F	38.521-2 implementation of FR2 UL demod OTA tests using single pol Rx TE	15.3.0
2019-06	RAN#84	R5-195432	0168	2	F	Update to 6.2.1.1 UE maximum output power - EIRP and TRP	15.3.0
2019-06	RAN#84	R5-195433	0169	2	F	Update to 6.2.1.2 UE maximum output power - Spherical coverage	15.3.0
2019-06	RAN#84	R5-195434	0140	1	F	Updates of MU and TT in TS 38.521-2	15.3.0
2019-06	RAN#84	R5-195435	0155	1	F	Core alignment with TS 38.101-2	15.3.0
2019-06	RAN#84	-	-	-	-	Administrative release upgrade to match the release of 3GPP TS 38.508-1 and TS 38.521-1 which were upgraded at RAN#84 to Rel- 16 due to Rel-16 relevant CR(s)	16.0.0
2019-09	RAN#85	R5-195695	0178	-	F	Change of TS 38.521-2 UL CA MOP Minimum conformance requirements	16.1.0
2019-09	RAN#85	R5-196069	0194	-	F	Introduction of absolute power tolerance for CA test cases	16.1.0
	RAN#85	R5-196165	0198	-	F	Correction of wrong spec reference numbers for TS 38.508-1	16.1.0
2019-09	RAN#85	R5-196236	0202	-	F	Correction to test procedure of TC 6.4.2.2 Carrier Leakage	16.1.0
2019-09	RAN#85	R5-196240	0206	-	F	Clarification on EVM test requirement for PUCCH and PRACH	16.1.0
2019-09	RAN#85	R5-196427	0208	-	F	Update of FR2 6.2.4 Configured transmitted power	16.1.0
2019-09	RAN#85	R5-196428	0209	-	F	Update of FR2 6.3.3.2 General ON_OFF time mask	16.1.0
2019-09	RAN#85	R5-196431	0211	-	F	Addition of FR2 6.2A.4 Configured transmitted power for 2UL CA	16.1.0
2019-09	RAN#85	R5-196433	0213	-	F	Addition of FR2 6.2D.4 Configured transmitted power for UL MIMO	16.1.0
2019-09	RAN#85	R5-196434	0214	-	F	Addition of FR2 6.3D.1 Minimum output power for UL MIMO	16.1.0
2019-09	RAN#85	R5-196594	0220	-	F	Addition of new test case 6.4A.2.1.2 Error vector magnitude for 3UL CA in FR2	16.1.0
	RAN#85	R5-196595	0221	-	F	Addition of new test case 6.4A.2.1.3 Error vector magnitude for 4UL CA in FR2	16.1.0
2019-09	RAN#85	R5-196650	0225	-	F	Update of Minimum conformance requirements and test configurations in TC 6.2.2	16.1.0
2019-09	RAN#85	R5-196810	0229	-	F	Update to TRP measurement grid section in TS 38.521-2	16.1.0
2019-09	RAN#85	R5-196950	0239	-	F	Corrections on clause 2 and 3 in 38.521-2	16.1.0
	RAN#85	R5-197384	0197	1	F	Update UL-MIMO to UL MIMO to align with RAN4 terminology in FR2	16.1.0
	RAN#85	R5-197385	0238	1	F	Update OBW FR2 test case	16.1.0
	RAN#85	R5-197386	0200	1	F	Alignment of clause 2 to 5 with the core spec	16.1.0
	RAN#85	R5-197387	0242	-	F	Integrating the QoQZ Procedures into 38.521-2	16.1.0
	RAN#85	R5-197388	0219	1	F	Addition of new test case 6.4A.2.1.1 Error vector magnitude for 2UL CA in FR2	16.1.0
	RAN#85	R5-197389	0222	1	F	Update of TC 6.3A.1.1 Minimum output power for 2UL CA	16.1.0
	RAN#85	R5-197390	0223	1	F	Addition of new test case 6.3A.1.2 Minimum output power for 3UL CA in FR2	16.1.0
	RAN#85	R5-197391	0224	1	F	Addition of new test case 6.3A.1.3 Minimum output power for 4UL CA in FR2	16.1.0
	RAN#85	R5-197392	0227	1	F	Update of Common Uplink Configuration table for PC3	16.1.0
	RAN#85	R5-197393	0212	1	F	Addition of FR2 6.3A.3 ON_OFF time mask for 2 UL CA	16.1.0
	RAN#85	R5-197394	0215	1	F	Addition of FR2 6.3D.3 General ON_OFF power for UL MIMO	16.1.0
	RAN#85	R5-197395	0199	1	F	Addition of new Annex N (normative): UE coordinate system	16.1.0
	RAN#85	R5-197500	0231	1	F	Update of Spurious Emissions TRP test procedure	16.1.0
	RAN#85	R5-197501	0233	1	F	Update of FR2 MUs in TS 38.521-2	16.1.0
	RAN#85	R5-197503	0230	1	F	Update of TRP measurement grids for spurious emissions	16.1.0
	RAN#85	R5-197529	0180	1	F	New Introduction of TC 6.2A.1.2.1 UE Maximum output power Spherical coverage 2UL CA	16.1.0
	RAN#85	R5-197530	0181	1	F	New Introduction of TC 6.2A.1.2.2 UE Maximum output power Spherical coverage 3UL CA	16.1.0
	RAN#85	R5-197531	0182	1	F	New Introduction of TC 6.2A.1.2.3 UE Maximum output power Spherical coverage 4UL CA	16.1.0
	RAN#85	R5-197532	0183	1	F	New Introduction of TC 6.4A.2.2.1 Carrier leakage 2UL CA	16.1.0
	RAN#85	R5-197533	0184	1	F	New Introduction of TC 6.4A.2.2.2 Carrier leakage 3UL CA	16.1.0
		R5-197534	0185	1	F	New Introduction of TC 6.4A.2.2.3 Carrier leakage 4UL CA	16.1.0
2019-09	RAN#85						
2019-09 2019-09	RAN#85	R5-197535	0189	1	F	Rel-16_NR_38.521-2_Addition of new TC 6.2A.1.1.1	16.1.0
2019-09 2019-09 2019-09	RAN#85 RAN#85	R5-197535 R5-197536	0189 0193	1	F	Additions to the SRS time mask for UL-MIMO test case	16.1.0
2019-09 2019-09 2019-09 2019-09	RAN#85	R5-197535	0189				

2019-09	RAN#85	R5-197539	0204	1	F	Correction to number of measurements of 6.4.2.3 In-band emissions	16.1.0
2019-09	RAN#85	R5-197540	0205	1	F	Correction to UBF in transmit modulation quality test cases	16.1.0
2019-09	RAN#85	R5-197541	0226	1	F	Update of FR2 A-MPR test case	16.1.0
2019-09	RAN#85	R5-197543	0190	1	F	Refsens test case updates	16.1.0
2019-09	RAN#85	R5-197544	0196	1	F	Introduction of beam correspondence to direct far field (DFF)	16.1.0
2019-09	RAN#85	R5-197545	0216	1	F	Updated to Annex A for RF FR2 tests	16.1.0
2019-09	RAN#85	R5-197546	0232	1	F	Integrating the Re-Positioning Concept into Annex K	16.1.0
2019-09	RAN#85	R5-197614	0191	1	F	Spurious test case updates	16.1.0
2019-09	RAN#85	R5-197642	0201	1	F	Correction to 6.5.2.1 SEM and 6.5.2.3 ACLR to consider MPR values	16.1.0
2019-09	RAN#85	R5-197643	0210	2	F	Addition of FR2 6.2A.2 MPR for 2 UL CA	16.1.0
2019-09	RAN#85	R5-197644	0177	2	F	Updates of MU and TT in TS 38.521-2	16.1.0
2019-09	RAN#85	R5-197645	0234	2	F	Addition of the connection setup in TS 38.521-2	16.1.0
2019-12	RAN#86	R5-198072	0247	-	F	Introduction of 4 New test cases 6.5A.1 Occupied bandwidth for CA	16.2.0
2019-12	RAN#86	R5-198073	0248	-	F	Introduction of 4 New test cases 6.5A.2.1 Spectrum Emission Mask for CA	16.2.0
2019-12	RAN#86	R5-198075	0249	-	F	Introduction of 4 New test cases 6.5A.2.2 Adjacent channel leakage ratio for CA	16.2.0
2019-12	RAN#86	R5-198078	0250	-	F	New Introduction of TC 6.2A.1.2.4 UE maximum output power - Spherical coverage 5UL CA	16.2.0
2019-12	RAN#86	R5-198079	0251	-	F	New Introduction of TC 6.2A.1.2.5 UE maximum output power - Spherical coverage 6UL CA	16.2.0
2019-12	RAN#86	R5-198080	0252	-	F	New Introduction of TC 6.2A.1.2.6 UE maximum output power - Spherical coverage 7UL CA	16.2.0
2019-12	RAN#86	R5-198081	0253	-	F	New Introduction of TC 6.2A.1.2.7 UE maximum output power - Spherical coverage 8UL CA	16.2.0
2019-12	RAN#86	R5-198210	0260	-	F	Addition of Common Uplink Configuration for PC1 in SA FR2 6.1	16.2.0
2019-12	RAN#86	R5-198381	0267	-	F	Introduction of beam correspondence side conditions	16.2.0
2019-12	RAN#86	R5-198385	0269	-	F	Update of minimum conformance requirements for SA FR2 7.4	16.2.0
2019-12	RAN#86	R5-198636	0276	-	F	General clause updated for FR2 spec	16.2.0
2019-12	RAN#86	R5-198730	0278	-	F	Correction of test requirements	16.2.0
2019-12	RAN#86	R5-199086	0262	1	F	CR to 38.521-2 on Measurement Grids for PC1 UEs	16.2.0
2019-12	RAN#86	R5-199087	0243	2	F	Updates of MU and TT in TS 38.521-2	16.2.0
2019-12	RAN#86	R5-199356	0245	1	F	Update of FR2 6.3.3.2 ON-OFF time mask	16.2.0
2019-12	RAN#86	R5-199357	0244	1	F	Update of FR2 6.3.1 minimum output power	16.2.0
2019-12	RAN#86	R5-199358	0263	1	F	CR to 38.521-2 on optimized search procedure for REFSENS	16.2.0
2019-12	RAN#86	R5-199359	0264	1	F	CR to 38.521-2 on optimized search procedure for RX Beam Peak Search	16.2.0
2019-12	RAN#86	R5-199360	0254	1	F	Updating incorrect note in test procedure	16.2.0
2019-12	RAN#86	R5-199361	0256	1	F	Spurious UL MIMO test case updates	16.2.0
2019-12	RAN#86	R5-199373	0265	1	F	Introduction of New TC 6.4A.2.3.1 In-band emissions for 2UL CA	16.2.0
2019-12	RAN#86	R5-199374	0266	1	F	Update to test case 6.3.3.4 PRACH time mask in FR2	16.2.0
2019-12	RAN#86	R5-199375	0257	1	F	Ref Sens UL MIMO test case updates	16.2.0
2019-12	RAN#86	R5-199376	0258	1	F	Alignment of clause 3 to 5 with the core spec	16.2.0
2019-12	RAN#86	R5-199461	0271	2	F	Further updates to the SRS time mask for UL-MIMO test case	16.2.0
2019-12	RAN#86	R5-199473	0282	-	F	Update to UE maximum output power - Spherical coverage	16.2.0
2019-12	RAN#86	R5-199483	0277	1	F	Update of applicability for Spherical coverage and Beam Correspondence test cases	16.2.0
2019-12	RAN#86	R5-199494	0281	1	F	Add section 4.5 Applicability and test coverage rules	16.2.0
2019-12	RAN#86	R5-199495	0246	1	F	Update of FR2 6.3.4.2 absolute power tolerance	16.2.0
2019-12	RAN#86	R5-199496	0240	1	F	Further updates to the absolute power tolerance for CA test cases	16.2.0
2019-12	RAN#86	R5-199504	0259	1	F	Addition of test requirements and update of minimum conformance requirements and test configurations for SA FR2 6.2.2	16.2.0
2019-12	RAN#86	R5-199548	0268	1	F	Updates to the beam correspondence TC	16.2.0
2019-12	RAN#86	R5-199579	0208	1	F	Update of quality of quiet zone validation procedure	16.2.0
2019-12	RAN#86	R5-199586	0279	1	F	Update on FR2 Spurious Test in 38.521-2	16.2.0
2020-03	RAN#87	R5-200319	0275	<u> </u>	F	CR to 38.521-2 on CDF/PDF Scaling Factor	16.3.0
2020-03	RAN#87	R5-200319	0289		F	CR to 38.521-2: Correction to TRP grid	16.3.0
2020-03	RAN#87	R5-200368	0292		F	Addition of new test case 6.3A.1.4 Minimum output power for 5UL	16.3.0
2020-03	RAN#87	R5-200369	0293		F	CA in FR2 Addition of new test case 6.3A.1.5 Minimum output power for 6UL CA in FR2	16.3.0
2020-03	RAN#87	R5-200372	0294		F	Addition of new test case 6.3A.1.6 Minimum output power for 7UL CA in FR2	16.3.0
2020-03	RAN#87	R5-200374	0295		F	Addition of new test case 6.3A.1.7 Minimum output power for 8UL CA in FR2	16.3.0
2020-03	RAN#87	R5-200375	0296	-	F	Addition of new test case 6.4A.2.1.4 Error vector magnitude for 5UL CA in FR2	16.3.0
2020-03	RAN#87	R5-200376	0297		F	Addition of new test case 6.4A.2.1.5 Error vector magnitude for 6UL CA in FR2	16.3.0
2020-03	RAN#87	R5-200377	0298		F	Addition of new test case 6.4A.2.1.6 Error vector magnitude for 7UL	16.3.0
2020-03	RAN#87	R5-200382	0300		F	CA in FR2 Addition of new test case 6.4A.2.1.7 Error vector magnitude for 8UL	16.3.0
2020-03	10#117	110-200302	0300	1	P	Addition of new test case 0.4A.2.1.7 Littor vector magnitude IOI 80L	10.3.0

						CA in FR2	
2020-03	RAN#87	R5-200383	0301		F	Update of test cases for Error vector magnitude for CA in FR2	16.3.0
2020-03	RAN#87	R5-200418	0302		F	Update of Operating bands and Channel arrangement of SA FR2 R15	16.3.0
2020-03	RAN#87	R5-200444	0303		F	Clarification of measurement interval of frequency error in FR2	16.3.0
2020-03	RAN#87	R5-200557	0309		F	Clarify absolute power tolerance for CA TP3	16.3.0
2020-03	RAN#87	R5-200602	0312		F	Updates to reference sensitivity test case	16.3.0
2020-03	RAN#87	R5-200656	0317		F	Correction of Editor's note of 6.2.2 and 6.3.2 of SA FR2 R15	16.3.0
2020-03	RAN#87	R5-201248	0318	1	F	Alignment of Table A.3.1-1 in 38.521-2 to core spec 38.101-2	16.3.0
2020-03	RAN#87	R5-200800	0319		F	Update of Standalone FR2 A-MPR test case	16.3.0
2020-03	RAN#87	R5-200894	0286	1	F	Correction to TC 6.3.4.4 Aggregate power tolerance	16.3.0
2020-03	RAN#87	R5-200910	0310	1	F	Beam correspondence TC message contents clarifications	16.3.0
2020-03	RAN#87	R5-200911	0285	1	F	Update of Clause 4 in TS 38.521-2	16.3.0
2020-03	RAN#87	R5-200980	0284	1	F	Correction of reference numbers in TS 38.521-2	16.3.0
2020-03	RAN#87	R5-200992	0291	1	F	Updates of MU and TT in TS 38.521-2 for Rel-16	16.3.0
2020-03	RAN#87	R5-201059	0305	1	F	Update of rx beampeak search	16.3.0
2020-03	RAN#87	R5-201060	0307	1	F	Update of absolute power tolerance for test point 3	16.3.0
2020-03	RAN#87	R5-201161	0313	1	F	Updates to test case relative power tolerance 6.3.4.3	16.3.0
2020-03	RAN#87	R5-201192	0283	1 3	F	Updates of MU and TT in TS 38.521-2	16.3.0
2020-03	RAN#87	R5-201244	0311	3	-	Correction of the FR2 RMC slot patterns for MOP test cases	16.3.0
2020-06 2020-06	RAN#88 RAN#88	R5-201328 R5-201330	0321 0323	-	F F	Add n261 to FR2 ACLR requirements Update to UBF command implementation for Relative power sub	16.4.0 16.4.0
2020.00		DE 201705	0225		E .	tests	16 4 0
2020-06	RAN#88	R5-201795	0325	-	F	Introduction of New TC 6.4A.2.2.4 Carrier leakage for 5UL CA Introduction of New TC 6.4A.2.2.5 Carrier leakage for 6UL CA	16.4.0
2020-06	RAN#88 RAN#88	R5-201796 R5-201797	0326 0327	-	F	Introduction of New TC 6.4A.2.2.6 Carrier leakage for 6UL CA Introduction of New TC 6.4A.2.2.6 Carrier leakage for 7UL CA	16.4.0 16.4.0
2020-06	RAN#88 RAN#88	R5-201797 R5-201811	0327	Ē	F	Introduction of New TC 6.4A.2.2.6 Carrier leakage for 70L CA	16.4.0
2020-06	RAN#88	R5-201811 R5-201812	0328	-	F	Introduction of New TC 6.4A.2.2.7 Carrier leakage for SOL CA	16.4.0
2020-00	RAN#88	R5-201813	0330	-	F	Introduction of New TC 6.4A.2.3.3 In-band emissions for 4UL CA	16.4.0
2020-00	RAN#88	R5-201814	0331	-	F	Introduction of New TC 6.4A.2.3.4 In-band emissions for 5UL CA	16.4.0
2020-06	RAN#88	R5-201815	0332	-	F	Introduction of New TC 6.4A.2.3.5 In-band emissions for 6UL CA	16.4.0
2020-06	RAN#88	R5-201835	0333	-	F	Correction of FR2 PUCCH EVM definition	16.4.0
2020-06	RAN#88	R5-201849	0334	-	F	Updating common uplink allocation for PC1	16.4.0
2020-06	RAN#88	R5-201850	0335	-	F	Cleaning up references to common uplink configuration	16.4.0
2020-06	RAN#88	R5-201851	0336	-	F	Updating test requirements of 6.2.3 AMPR for NS_201	16.4.0
2020-06	RAN#88	R5-202045	0342	-	F	Correction of test metric in minimum conformance requirements and	16.4.0
2020-06	RAN#88	R5-202046	0343	-	F	some test style in 6.3.2 of SA FR2 R15 Correction of uplink configuration table number in minimum	16.4.0
						conformance requirements and test requirement table of 7.4 of SA FR2 R15	
2020-06	RAN#88	R5-202120	0346	-	F	CR to 38.521-2 to correct Clenshaw-Curtis Weight Equations	16.4.0
2020-06	RAN#88	R5-202122	0348	-	F	CR to 38.521-2 to clarify the applicability of QoQZ validation	16.4.0
2020-06	RAN#88	R5-202135	0354	-	F	Update to 6 test cases 6.5A.2.1.x Spectrum Emission Mask for 3 to 8 UL CA	16.4.0
2020-06	RAN#88	R5-202137	0356	-	F	Update to 6 test cases 6.5A.2.2.x Adjacent channel leakage ratio for 3 to 8 UL CA	16.4.0
2020-06	RAN#88	R5-202447	0367	-	F	Editorial correction to the test requirement of in-band blocking	16.4.0
2020-06	RAN#88	R5-202450	0368	-	F	Correction of Spectrum Emission Mask CA test cases	16.4.0
2020-06	RAN#88	R5-202504	0372	-	F	CR on EVM Window Centre Timing Definition in FR2	16.4.0
2020-06	RAN#88	R5-202720	0345	1	F	CR to 38.521-2 to correct Clenshaw-Curtis Weights at the Poles for CDF/CCDF	16.4.0
2020-06	RAN#88	R5-202722	0364	1	F	Additions to Initial Conditions and Messages for SRS time mask with UL MIMO	16.4.0
2020-06	RAN#88	R5-202723	0337	1	F	Aligning test procedure for Rx beam peak direction	16.4.0
2020-06	RAN#88	R5-202724	0341	1	F	Alignment of section 3 and 5 with core spec of SA FR2 R15	16.4.0
2020-06	RAN#88	R5-202808	0365	1	F	Receiver characteristics testing update to 38.521-2	16.4.0
2020-06	RAN#88	R5-202824	0351	1	F	Update to test case 6.5A.1.1 Occupied bandwidth for 2UL CA	16.4.0
2020-06	RAN#88	R5-202825	0353	1	F	Update to test case 6.5A.2.1.1 Spectrum Emission Mask for 2UL CA	16.4.0
2020-06	RAN#88	R5-202826	0355	1	F	Update to test case 6.5A.2.2.1 Adjacent channel leakage ratio for 2UL CA	16.4.0
2020-06	RAN#88	R5-202827	0371	1	F	Update to 6 test cases 6.5A.1.x Occupied bandwidth for 3 to 8 UL CA	16.4.0
2020-06	RAN#88	R5-202828	0338	1	F	Updating SRS config table in test case 6.3D.3.4	16.4.0
2020-06	RAN#88	R5-202885	0322	1	F	Add NS 202 requirements to FR2 additional spurious emission test case	16.4.0
2020-06	RAN#88	R5-202893	0349	1	F	Editorial correction of test case 6.5.1 Occupied bandwidth to align with core spec	16.4.0
2020-06	RAN#88	R5-202894	0350	1	F	Editorial correction of Tx test cases for Out of band emission to align with core spec	16.4.0
2020-06	RAN#88	R5-202895	0357	1	F	Clarification of disabling Tx diversity for FR2 UE for SA FR2 testing	16.4.0
2020-06	RAN#88	R5-202896	0358	1	F	Updates of Test Points of Tx CA test cases	16.4.0
2020-06	RAN#88	R5-202897	0360	1	F	Correction on txDirectCurrentLocation in FR2 SA tests	16.4.0

2020-06	RAN#88	R5-202898	0370	1	F	Update on transmit modulation quality test cases	16.4.0
2020-06	RAN#88	R5-202899	0361	1	F	Update to SA FR2 Receiver Spurious Emission Test Case	16.4.0
2020-06	RAN#88	R5-202943	0363	1	F	CR to 38.521-2: On the order of test steps for output power	16.4.0
0000.00	DANUOO	DE 00000	0050		_	dynamics test cases	10.1.0
2020-06	RAN#88	R5-202968	0359	1	F	Core spec alignment of k1 value for RF test cases	16.4.0
	RAN#88	R5-202990	0362	2	F	Updates of FR2 MU and TT in TS 38.521-2	16.4.0
2020-06	RAN#88	R5-203117	0347	2		CR to 38.521-2 to properly define Link and Meas Angles	16.4.0
2020-09	RAN#89	R5-203292	0373	-	F	Clarification of Interferer frequency selection in FR2 IBB test case 7.6.2	16.5.0
2020-09	RAN#89	R5-203875	0392	-	F	Alignment of general sections with core spec of SA FR2 R15	16.5.0
2020-09	RAN#89	R5-203969	0394	-	F	Updating beam correspondence capability	16.5.0
2020-09	RAN#89	R5-204264	0412	-	F	Editorial correction of ACLR CA test cases	16.5.0
2020-09	RAN#89	R5-204265	0413	-	F	Editorial correction of Annex C.3 Connection	16.5.0
2020-09	RAN#89	R5-204266	0414	-	F	Update of FR2 OBW test case	16.5.0
2020-09	RAN#89	R5-204713	0382	1	F	Correction to test configuration for Carrier leakage for CA	16.5.0
2020-09	RAN#89	R5-204714	0383	1	F	Correction to TC 6.4A.2.3.1 In-band emissions for 2UL CA	16.5.0
2020-09	RAN#89	R5-204715	0384	1	F	Correction to test cases 6.4A.2.3.x In-band emissions for 3 to 6 UL CA	16.5.0
2020-09	RAN#89	R5-204716	0385	1	F	Introduction of New TC 6.4A.2.3.6 In-band emissions for 7UL CA	16.5.0
2020-09	RAN#89	R5-204717	0386	1	F	Introduction of New TC 6.4A.2.3.7 In-band emissions for 8UL CA	16.5.0
2020-09	RAN#89	R5-204763	0393	1	F	Miscellaneous corrections due to core spec alignment	16.5.0
2020-09	RAN#89	R5-204764	0415	1	F	Update of Tx signal quality test cases	16.5.0
2020-09	RAN#89	R5-204765	0395	1	F	Addition of UL power setting for Rx test cases	16.5.0
2020-09	RAN#89	R5-204856	0403	1	F	CR to update MU and TT in 38.521-2	16.5.0
2020-09	RAN#89	R5-204857	0380	1	F	Beam correspondence - SRS configuration corrections in section	16.5.0
2020-09	RAN#89	R5-204858	0397	1	F	6.6.1 CR to 38.521-2 to update Absolute Power Tolerance for CA on the	16.5.0
2020-09	RAN#89	R5-204859	0401	1	F	order of test steps CR to TS 38.521-2: Correction to MB relaxation minimum	16.5.0
						requirements	
2020-09	RAN#89	R5-204860	0406	1	F	CR to 38.521-2 to adjust the test step sequences	16.5.0
2020-09	RAN#89	R5-204861	0407	1	F	CR to 38.521-2 to allow vendor declarations related to beam peak searches	16.5.0
2020-09	RAN#89	R5-204862	0408	1	F	CR to 38.521-2 on QoQZ Verification Clarification	16.5.0
2020-09	RAN#89	R5-204863	0411	1	F	FR2 Minimum output power MU updates	16.5.0
2020-09	RAN#89	R5-204864	0417	1	F	FR2 EIRP OFF power MU updates	16.5.0
2020-09	RAN#89	R5-204865	0379	1	F	Beam correspondence - SRS configuration corrections in annex K.1.1	16.5.0
2020-09	RAN#89	R5-204914	0388	1	F	Updates to test case 6.3.4.3, relative power tolerance	16.5.0
2020-09	RAN#89	R5-204915	0398	1	F	CR to 38.521-2 to update Transmit OFF Power	16.5.0
2020-09	RAN#89	R5-204916	0399	1	F	CR to TS 38.521-2: Correction to time mask requirements	16.5.0
2020-09	RAN#89	R5-204917	0402	1	F	Clean up complete status for FR2 SA test cases	16.5.0
2020-09	RAN#89	R5-204918	0404	1	F	Update to UE maximum output power for CA	16.5.0
2020-09	RAN#89	R5-204919	0410	1	F	FR2 Minimum output power measurement period definition	16.5.0
2020-09	RAN#89	R5-204920	0389	1	F	FR2 RefSens and EIS spherical PC3 MBR table update	16.5.0
2020-09	RAN#89	R5-204921	0396	1	F	Addition of modified MPR behaviour	16.5.0
2020-09	RAN#89	R5-204922	0400	1	F	CR to TS 38.521-2: Annex F EIRP OFF Power	16.5.0
2020-09	RAN#89	R5-204923	0409	1	F	CR to TS 38.521-2 on DUT alignment options	16.5.0
2020-09	RAN#89	RP-201671	0418	-	F	Adding FR2 PDCCH Aggregation Level in Annex C.3	16.5.0
2020-12	RAN#90	R5-205259	0420	-	F	Addition of new test case 6.4D.3 Time alignment error for UL MIMO in FR2	16.6.0
2020-12	RAN#90	R5-205260	0421	-	F	Addition of new test case 6.5D.1 Occupied bandwidth for UL MIMO in FR2	16.6.0
2020-12	RAN#90	R5-205496	0422	<del> _</del>	F	Alignment of general sections with core spec	16.6.0
		1110 200430	0722	Ļ.	F		16.6.0
			0423	-			
2020-12 2020-12 2020-12	RAN#90 RAN#90	R5-205497 R5-205536	0423 0427	-	F	Correction of minimum conformance requirements for 6.2.2 MPR Aligning tested subframe numbers with defined RMC in test case	16.6.0
2020-12	RAN#90	R5-205497		-		Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test	
2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90	R5-205497 R5-205536 R5-205573	0427 0428	-	F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case	16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90	R5-205497 R5-205536 R5-205573 R5-205711	0427 0428 0431	- - - -	F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up	16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497 R5-205536 R5-205573 R5-205711 R5-205811	0427 0428 0431 0433	- - - -	F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA	16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90	R5-205497 R5-205536 R5-205573 R5-205711	0427 0428 0431	- - - - - - -	F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC	16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497 R5-205536 R5-205573 R5-205711 R5-205811 R5-205812 R5-205854	0427 0428 0431 0433 0434 0438	- - - - - - -	F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3	16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497           R5-205536           R5-205573           R5-205711           R5-205811           R5-205812           R5-205854           R5-205809	0427 0428 0431 0433 0434 0438 0439	- - - - - - - - - - - -	F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3 Update of in-band emission and carrier leakage test cases	16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497           R5-205536           R5-205573           R5-205711           R5-205811           R5-205812           R5-205854           R5-206009           R5-206206	0427 0428 0431 0433 0434 0438	- - - - - - - - - - - - - - - - - -	F F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3 Update of in-band emission and carrier leakage test cases Update of occupied bandwidth test case	16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497           R5-205536           R5-205573           R5-205711           R5-205811           R5-205812           R5-205854           R5-205809	0427 0428 0431 0433 0434 0438 0439 0439	- - - - - - - - - - - - - 1	F F F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3 Update of in-band emission and carrier leakage test cases Update of occupied bandwidth test case Correction of Annex F for absolute power tolerance for CA Correction of MBW for output power dynamics TCs 6.3.x and ACLR	16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497           R5-205536           R5-205573           R5-205711           R5-205811           R5-205812           R5-205854           R5-206009           R5-206206           R5-206210           R5-206644	0427 0428 0431 0433 0434 0438 0439 0448 0449 0437	- - - 1	F F F F F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3 Update of in-band emission and carrier leakage test cases Update of occupied bandwidth test case Correction of Annex F for absolute power tolerance for CA Correction of MBW for output power dynamics TCs 6.3.x and ACLR TC 6.5.2.3	16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0         16.6.0
2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12 2020-12	RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90 RAN#90	R5-205497           R5-205536           R5-205573           R5-205711           R5-205811           R5-205812           R5-205854           R5-206009           R5-206206           R5-206210	0427 0428 0431 0433 0434 0438 0439 0448 0449	-	F F F F F F F	Aligning tested subframe numbers with defined RMC in test case 6.3.4.3 Adding a new note in test configuration table for ACLR and SEM test case FR2 EIS editor's note clean up Correction to Carrier leakage for CA Correction to In-band emissions for CA Correction of transmission gap for relative power tolerance TC 6.3.4.3 Update of in-band emission and carrier leakage test cases Update of occupied bandwidth test case Correction of Annex F for absolute power tolerance for CA Correction of MBW for output power dynamics TCs 6.3.x and ACLR	16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0 16.6.0

2020-12	RAN#90	R5-206821	0442	1	F	CR to 38.521-2 on ETC Testing	16.6.0
2020-12	RAN#90	R5-206822	0445	1	F	Minimum output power updates	16.6.0
2020-12	RAN#90	R5-206823	0446	1	F	FR2 time masks updates	16.6.0
2020-12	RAN#90	R5-206824	0443	1	F	Update FR2 TRx MU and TT in 38.521-2	16.6.0
2020-12	RAN#90	R5-206825	0444	1	F	Minimum output power measurement uncertainties and test tolerances	16.6.0
2020-12	RAN#90	R5-206826	0447	1	F	FR2 Time masks updates	16.6.0
2020-12	RAN#90	R5-206865	0429	1	F	Update on Test points of FR2 Transmit OFF power for CA	16.6.0
2020-12	RAN#90	R5-206866	0432	1	F	Adding NS202 and NS203 to MOP and Spurious	16.6.0
2020-12	RAN#90	R5-206867	0435	1	F	Addition of 6.5D.2.1 Spectrum Emission Mask for UL MIMO in FR2	16.6.0
2020-12	RAN#90	R5-206868	0436	1	F	Addition of 6.5D.2.2 Adjacent channel leakage ratio for UL MIMO in FR2	16.6.0

## History

	Document history									
V16.4.0	October 2020	Publication								
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V16.6.0	February 2021	Publication								